# **TECHNICAL MANUAL**

# GENERAL SUPPORT AND DEPOT MAINTENANCE MANUAL

TEST SET, NAVIGATIONAL COMPTUER-CONTROL INDICATOR AN/ASM-386 (FSN 6625-404-3280)

HEADQUARTERS, DEPARTMENT OF THE ARMY FEBRUARY 1972

#### WARNING

Be careful when working with the 115-volt power connections. SERIOUS INJURY or DEATH may result from contact with these terminals.

# CAUTION

This equipment contains highly sophisticated, complicated circuitry. Maintenance personnel should not attempt any maintenance without reading and fully understanding the applicable section relating to that maintenance.

HEADQUARTERS, DEPARTMENT OF THE ARMY WASHINGTON, D.C., 18 February 1972

# GENERAL SUPPORT AND DEPOT MAINTENANCE MANUAL TEST SET, NAVIGATIONAL COMPUTER-CONTROL INDICATOR AN/ASM-386 (FSN 6625-404-3280)

#### NOTE

This volume contains chapters 1 through 5 and appendixes A and B. Wire lists, appendix C, are contained in TM 11-6625-2441-45-2.

			Paragraph	Page
CHAPTER	1.	INTRODUCTION		-
		Scope	. 1-1	1-1
		Indexes of publications	. 1-2	1-1
		Reporting of equipment publication improvements	1-3	1-1
CHAPTER	2.	PRINCIPLES OF OPERATION		
Section	Ι.	Block diagram analysis		
		General		2-1
		Test set, general description	2-2	2-2
		Tape reader control		2-4
		Error detection and control	. 2-4	2-4
		Error display	. 2-5	2-4
		Self test	. 2-6	2-4
		Computer memory test	. 2-7	2-5
		Computer arithmetic and control logic test		2-5
		Computer interface test	. 2-9	2-5
		Application of power		2-6
	II.	Detail circuit analysis		
		Memory fill and verify	. 2-11	2-6
		Load and read-compare		2-14
		Branch control function		2-17
		Computer and control-indicator interface test		2-19
		Front panel indicators and error control		2-27
		Clock generator		2-28
		Power supply 2A1PS1		2-30
		Power control and distribution		2-32
	111.	Tape format and control		
		Self-test tape operation	. 2-19	2-33
		Tape control and processing		2-35
		Program listing		2-47
CHAPTER	3.	GENERAL SUPPORT MAINTENANCE		
Section	Ι.	General		
		Scope	. 3-1	3-1
		Test equipment, tools, and materials required		3-1
	П.	Troubleshooting		
		Troubleshooting procedures	3-3	3-3
		Troubleshooting chart		3-3
		Adapter, Self Test MS-8586/ASM-386 3A4, continuity and		
		resistance measurements	3-5	3-6

No.11-6625-2441-45

Paragraph Page

			Falaylaph	Fage
	III.	Removal and replacement		
		Removal and replacement of indicators 2A1DSI through 2A1DS9	3-6	3-7
		Removal and replacement of switch 2A1S1		3-11
		Removal and replacement of switch 2A1S2		3-11
		Removal and replacement of elapsed-time meters 2A1M1 -and 1A1A5M1	3-9	3-11
			5-5	5-11
		Removal and replacement of front panel connectors 2A1J3	0.40	0.44
		through 2A1J12		3-11
		Removal and replacement of filter 2A1J2		3-12
		Removal and replacement of filter 2A1J1	3-12	3-12
		Removal and replacement of circuit breakers 2A1CB1 through 2A1CB4	3-13	3-12
		Removal and replacement of blower 2A1B1	3-14	3-13
		Removal and replacement of blowers 2A1B2 and 2A1B3	3-15	3-13
		Removal and replacement of capacitors 2A1C1 through 2A1C4		3-13
		Removal and replacement of component board 2A1A4	3-17	3-14
				3-14
		Removal and replacement of switches 2A1S3 through 2A1S6		
		Removal and replacement of test point connectors 2A1J13 through 2A1J63		3-15
		Removal and replacement of transformer 2A1T1		3-15
		Removal and replacement of reactor 2A1L1	3-21	3-15
		Removal and replacement of terminal board 2A1TB1		3-16
		Removal and replacement of bus bars 2A1W2 and 2A1W3		3-16
		Removal and replacement of card cage connectors		3-17
		Removal and replacement of connector plate		3-17
		Removal and replacement of card cage 2A1A3	3-26	3-18
		Removal and replacement of card cages 2A1A1, 2A1A2, and 1A1A1		
		through 1A1A4	3-27	3-18
		Removal and replacement of indicators 1A1A5DS1 through A1A5DS6		
		and 1A1A5DS9	3-28	3-19
		Removal and replacement of switches 1A1A5S2, 1A15S3, 1A1A5S8,		
		1A1A6S5, and 1A1A6S6	3-29	3-21
			5-29	5-21
		Removal and replacement of digital display indicators 1A1A5DS7 and	0.00	0.04
		1A1A5DS8		3-21
		Removal and replacement of indicators 1A1A5DS10 and 1A1A5DS11		3-22
		Removal and replacement of switches 1A1A5S4, 1A1A5S6, and 1A1A5S7	3-32	3-22
		Removal and replacement of switches 1A1A5S1, 1A1A6S2, and 1A1A6S3	3-33	3-22
		Removal and replacement of s-witches 1A1A6S7 through 1A1A6S17		3-23
		Removal and replacement of switch 1A1A6S1	3-35	3-23
		Removal and replacement of thumbwheel switches 1A1A6S4 and 1A1A5S5		3-23'
		Removal and replacement of panel lockout switch 1A1S1		3-24
		Removal and replacement of blower 1A1BL and 1A1B2		3-24
		Removal and replacement of capacitors 1 A1Cl and 1A1C2	3-39	3-24
		Removal and replacement of oscillator 1A1Y1	3-40	3-25
		Removal and replacement of connectors 1A1J1 through 1A1J11		3-25
		Removal and replacement of connectors 3A1-2J1 through 3A4-2J8,	• • • •	0 20
		3A4-5J15, 3A4-2J16, and 3A4-3J1	3-42	3-25
		Removal and replacement of bumpers and cable clamps		3-27
		Removal and replacement of resistor SA1RI	3-44	3-27
		Removal and replacement of component board 3A4A1	3-45	3-27
		Removal and replacement of bus bar 3A4WI	3-46	3-27
		Connector repair and replacement	3-47	3-27
CHAPTER	4	DEPOT MAINTENANCE		
Section		General		
Occion			4-1	4-1
		Scope of depot maintenance		
		Tools, test equipment, and materials required	4-2	4-1
	II.	Troubleshooting		
		General	4-3	4-2
		Power supply 2A1PS1 fault isolation	4-4	4-2
		Power supply 2A1PS1 test procedure	4-5	4-2
		Special purpose electrical cable assembly checks and troubleshooting		4-11
		Power supply 2A1PS1 troubleshooting chart	4-7	4-11
		r on or oupply $Lr(r)$ or a consistent of an and $r$ of a construction of the const	<i>ч і</i>	-7 11

# TM 11-6625-2441-45-1

Paragraph Page

		Paragraph	Page
II	. Removal, replacement, repair, and adjustments		
	General	4-8	4-14
	Instructions for removal and replacement of power supply 2A1PS1		
	modules, assemblies, and components	4-9	4-14
	Removal and replacement of semi-conductors 2A1PS1CR12 and		
	2A1PS1Q1		4-17
	Removal and replacement of +5 V crowbar 2A1PS1VR7W2		4-18
	Removal and replacement of modules 2A1PS1A2 through 2AIPS1A5		4-18
	Removal and replacement of connectors 2A1PS1J1 and 2A1PS1J2		4-18
	Removal and replacement of bus bar 2A1PS1W1		4-18
	Removal and replacement of voltage regulators 2A1PS1VR1 and 2A1PS1VR8	4-15	4-19
	Removal and replacement of voltage regulators 2A1PS1VR2, 2A1PS1VR3,		
	2A1PS1VR4, and 2A1PS1VR6		4-19
	Removal and replacement of filters 2A1PS1FL1 through 2A1PS1FL12		4-19
	Removal and replacement of component assembly 2A1PS1A6		4-20
	Removal and replacement of relay 2A1PS1K1		4-20
	Removal and replacement of transformer rectifier assembly 2A1PS1A1		4-20
	Removal and replacement of diode assemblies 2A1PS1A1Z3 and 2A1PS1A1Z4		4-21
	Removal and replacement of diode assemblies 2A1PS1A1Z1 and 2A1PS1A1Z2		4-21
	Removal and replacement of transformer 2A1PS1T1		4-21
	Removal and replacement of capacitors 2A1PS1C1 through 2A1PS1C5		4-21
	Removal and replacement of inductor 2A1PS1L3	4-25	4-22
	Removal and replacement of inductors 2A1PS1L1 and 2AI PS1 L2		4-22
	Removal and replacement of relay 2A1PS1K2		4-22
	Removal and replacement of heat sink 2A1PS1MP4		4-22
	Removal and replacement of +5 V switching regulator 2A1PS1VR7		4-23
	Removal and replacement of diode 2A1PS1VR7CR1		4-23
	Removal and replacement of transistor 2A1PS1VR7Q2		4-23
	Removal and replacement of inductor 2A1PS1VR7		4-24
	Removal and replacement of regulator controller assembly 2A1PS1VR7A1		4-24
	Removal and replacement of resistors 2A1PSIVR7R3 and 2A1PS1VR7R4	4-34	4-24
	Removal and replacement of bus bars 2A1PSIVR7W1 and 2A1PSIVR7W2		
	and insulated standoffs		4-24
	Removal and replacement of capacitor 2A1PS1VR7C3 and clip	4-36	4-25
	Removal and replacement of capacitor bracket and capacitors 2A1PS1VR7C1		
	and 2A1PS1VR7C2		4-25
	Removal and replacement of transistor 2A1PSIVR7Q1		4-26
	Special purpose electrical cable assembly repair		4-26
n	Power supply 2AIPS1 adjustments	4-40	4-26
IV	. Depot overhaul standards		4 07
	Applicability of depot overhaul standards		4-27
	Applicable references		4-27
	Test facilities required		4-27
	Test procedures	4-44	4-27
			- 4
CHAPTER 5	. FINAL ILLUSTRATIONS		5-1
	. REFERENCES		A-1
AFFENDIA P	. REFERENCES		A-1
E	. PROGRAM LISTING		B-1
	. Introduction		
200001	General	B-1	B-1
	Program listing column headings and entries		B-1
	How to use the self-test program listing		B-3
I	. Self-test program	20	20
•			

# LIST OF ILLUSTRATIONS

Figure	Title	Page
2-1	Test Set, Navigational Computer-Control Indicator AN/ASM-386, block diagram	2-1
2-2	Test Set, Navigational Computer-Control Indicator AN/ASM-386, functional block diagram	2-3
2-3	Memory fill and verify, timing diagram	
2-4 (1)	Worst case memory fill and verify, timing diagram (part 1 of 3)	
2-4 (2)	Worst case memory fill and verify, timing diagram (part 4 of 3)	
2-4 (3)	Worst case memory fill and verify, timing diagram (part 2 of 3)	
2-5	Single instruction memory fill and verify, timing diagram	
2-6	Read-compare program, flow chart	
2-7	Computer register loading, timing diagram	
2-8	Read-compare, timing diagram	
2-9	Read-compare reiteration, timing diagram	
2-10	Branch control function, flow chart	
2-11	Analog processing test, data flow block diagram	
2-12	Analog processing - synchro voltage signals, data flow block diagram	
2-13	Analog processing - low level signals, data flow block diagram	
2-14	Load discrete word, data flow block diagram	
2-15	TACAN and control-indicator data processing, data flow block diagram	
2-16	TACAN data to compare, timing diagram	
2-17	Control-indicator position fix test, data flow block diagram	
2-18	Control-indicator MODE switch test, data flow block diagram	
2-19	Control-indicator input test, data flow block diagram	
2-20	Control-indicator input-output test, data flow block diagram	
2-21	Platform interface test, data flow block diagram	
2-22	Front panel indicators and error control, data flow chart	
2-23	Test set clock system with computer clock running, timing diagram	
2-24	Two-MHz-clock square wave, timing diagram	
2-25	Clock generation during self-test and control-indicator checkout, timing diagram.	
2-26	Test panel, Signal Conditioning Unit TS-2913/ASM-386	
2-27	Tape direction, flow diagram	
2-28	Tape search, timing diagram	
2-29	Typical tape format check, timing diagram	
2-30	Byte shift register, timing diagram	
2-31	Load test address register, data flow block diagram	
2-32	Load instruction register, data flow diagram	
3-1	Adapter, Self Test MX-8586/ASM-386, resistor location diagram	
3-2 (1)	Signal Conditioning Unit TS-2913/ASM-386, exploded view (part 1 of 3)	
3-2 (2)	Signal Conditioning Unit TS-2913/ASM-386, exploded view (part 2 of 3)	
3-2 (3)	Signal Conditioning Unit TS-2913/ASM-386, exploded view (part 3 of 3)	
3-3	Logic Control Unit TS-2912/ASM-286, exploded view	
3-4	Adapter, Self-Test MX-8586/ASM-386, exploded view	
3-5	Special purpose electrical cable assembly, typical shielded cable configuration	
	and connector removal diagram	3-30
3-6	Connector 2W6P2, configuration diagram	
3-7	Termi-Point service tool loading	
3-8	Extractor-locator tool	
3-9	Preparing Termi-Point service tool for use	
3-10	Applying clip to connector pin	
4-1	Power Supply 2A1PS1, Test Setup	4-3

# LIST OF ILLUSTRATIONS (Continued)

Figure	Title	Page
4-2 (1)	Power supply 2A1PS1, exploded view (part 1 of 3)	4-15
4-2 (2)	Power supply 2A1PS1, exploded view (part 2 of 3)	4-16
4-2 (3)	Power supply 2A1PS1, exploded view (part 3 of 3)	4-17
5-1	MIL STD resistor and capacitor color code mar Kings	
5-2	NOT USED	
5-3	Memory fill and verify, block diagram	5-1
5-4	Load and read-compare functional block diagram	5-2
5-5	Power supply 2A1PS1, functional schematic diagram	5-3
5-6 (1)	Power control and distribution, functional schematic diagram (part 1 of 2)	5-4
5-6 (2)	Power control and distribution, functional schematic diagram (part 2 of 2)	5-5
5-7	Tape control and processing, functional block diagram	5-6
5-8	Adapter, Self Test MX-8586/ASM-386, schematic diagram	5-7
5-9 (1)	Special purpose electrical cable assembly, schematic diagram (part 1 of 3)	5-8
5-9 (2)	Special purpose electrical cable assembly, schematic diagram (part 2 of 3)	5-9
5-9 (3)	Special purpose electrical cable assembly, schematic diagram (part 3 of 3)	5-10
5-10	Power supply 2A1PSI, parts location diagram	5-11

#### **CHAPTER 1**

#### 1-1. Scope

a. This manual covers general support and depot maintenance procedures for Test Set, Navigational Computer-Control Indicator AN/ASM386 (test set). Circuit analyses, troubleshooting and removal and replacement, and testing procedures are also included. The complete manual consists of three manuals. TM 11-6625-2441-45-1 contains the introductory data, principles of operation, maintenance chapters, list of references, and the program listing; TM 11-6625-2441-45-2 and TM 11-6625-2441-45-3 contains the wire lists.

b. Publications that complete coverage for this equipment include three other manuals: TM 11-6625 2441-12, Operator's and Organizational Maintenance Manual; TM 11-6625--2441-20P, Organizational Repair Parts and Special Tools List; and TM 11-6625-2441-45P, General Support and Depot Maintenance Repair Parts and Special Tools List.

#### 1-2. Indexes of Publications

a. DA Pam 310-4. Refer to DA Pam 310-4 to determine whether there are new editions, changes, or additional publications pertaining to the equipment.

b. DA Pam 310-7. Refer to DA Pam 310-7 to determine whether there are modification work orders (MWO's) pertaining to the equipment.

NOTE Applicable forms and records are covered in TM 11-6625-2441-12.

# 1-3. Reporting of Equipment Publication Improvements

The reporting of errors, omissions, and recommendations for improving this publication by the individual user is encouraged. Reports should be submitted on DA Form 2028 (Recommended Changes to Publications) and forwarded direct to Commanding General, U.S. Army Electronics Command, ATTN: AMSEL-MA-AN, Fort Monmouth, N.J. 07703.

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#### **CHAPTER 2**

#### **PRINCIPLES OF OPERATION**

#### Section I. BLOCK DIAGRAM ANALYSIS

#### 2-1. General

The test set processes and distributes signals necessary to test navigational computers and control-indicators, and to perform a self-test operation. The processing operation is controlled by data received from the tape reader. The test set uses tape data and data from the unit under test to perform specific routines as required by particular tests. The relationship of Logic Control Unit TS-2912/ASM-386 (LCU), Signal Conditioning Unit TS-2913/ASM-386 (SCU), tape reader, and Adapter, Self Test MX-8586/ ASM-386 (self-test adapter) is illustrated in figure 2-1. The functions of the LCU, SCU, and selfadapter are discussed in the following test subparagraphs. Reference designations for the LCU, SCU, and self-test adapter are 1A1, 2A1, and 3A4 respectively. All subassemblies of these units are prefixed with the unit designation.

a. LCU. The speed and direction of the tape reader drive are determined by control signals received from the LCU. The tape reader applies tape data to the LCU where the type of data is determined and processed accordingly. The processed data is used in the LCU and is applied to the SCU and self-test adapter or the unit under test. Power for operation of the LCU is provided by the SCU. Test data indicating a go or no-go condition of the unit under test, or the test set, is received from the SCU. The condition of the test data is displayed in the LCU front panel displays and indicators and, when so indicated, to the tape reader as a stop or rerun signal. The control-indicator signal and power supply voltages are applied through the LCU to the SCU. The power supply voltages are connected to the external monitoring equipment (oscilloscope and digital voltmeter) and the signals are processed and returned to the LCU for display. Clock

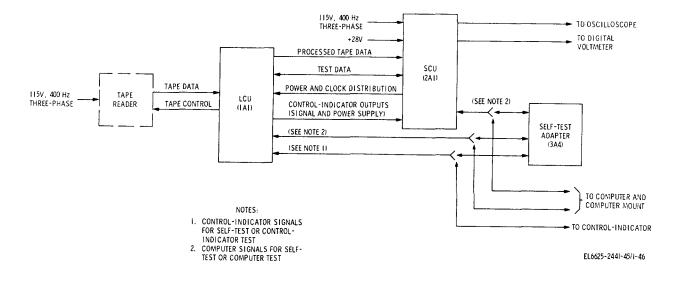


Figure 2-1. Test Set, Navigational Computer-Control Indicator AN/ASM-386, block diagram.

signals required for operation of the test set are generated in the LCU and distributed to the SCU, and to the unit under test upon demand.

*b. SCU.* The SCU receives 115 Vac and +28 V primary power and distributes operating voltages.

Connection of the navigational computer, control indicator, and test set voltages to external monitoring equipment is provided through front panel POWER MONITOR switch. Processed data from the LCU which requires further modification is processed in the SCU and applied to the unit under test. Processed data is also used by the SCU, in conjunction with data from the unit under test, to perform various test routines. Test data signals are applied to the LCU for processing go/no-go indications.

*c.* Self-test Adapter. The self-test adapter is used to provide continuity of signals between the LCU and the SCU during self-test of the test set.

Resistors in the self-test adapter provide loads for signals as required.

# 2-2. Test Set, General Description

(fig. 2-2)

a. Interface. The test set dynamically simulates any signal which a computer or control indicator normally sees during system operation. Each computer or control-indicator input and output is analyzed for correctness against the known correct respective output or input stored on the program tape. Organization of the computer external avionics subassemblies servicing program enables the test set to simulate only one of these external avionics systems at a time, which greatly minimizes the test set complexity.

b. Major and Minor Tests. The tape program is made up of major and minor test routines. Each major test can have a maximum of 100 minor tests. A major test is usually associated with a major function of the test sets, computer, or control-indicator. The program is organized on a test priority level; the most important functional areas are analyzed first. With the computer, the test set exercises the computer memory fill and read electronics first. Once the test set has established that the memory and associated computer electronics are in working order, the program loads many operational subroutines into the computer memory for use in subsequent fault-diagnostic programs.

(1) Each test routine does not necessarily yield a definite result which leads directly to the faulty assembly. In some cases, the faulty assembly must be determined through deductive test techniques. In this technique, the operator selects the next test number by referring to the appropriate maintenance manual. The operator uses this manual by finding the page associated with the major or minor test number displayed on the LCU panel. Here the test result which compares with the test result displayed on the LCU panel is selected. Associated with the selected test result are instructions which give direction for the fault-diagnosis procedure.

(2) Each major functional requirement of the test set, computer, and the control-indicator is assigned a major test number. The test set is capable of handling 100 major test numbers.

Each major test is subdivided into minor tests (1 up to 100). The TEST NUMBER/MAJOR, MINOR indication is the basis of correlation between the program tape and the appropriate maintenance manual.

*c. Program Tapes.* All programs essential for maintenance of the test set, computer, and controlindicator are provided by tapes. Each tape is programmed to include the functions that simulate the related equipment of the unit under test. The computer tape contains data that simulates the signals (input and output) of the appropriate associated avionics. The control indicator tape is programmed to simulate input and output signals that interface with the control indicator in normal system applications. Self-test, tape includes functions which are required to exercise portions of the computer and control indicator.

(1) *Computer tapes.* Computer test and diagnostic operations are programmed for both test set and computer control. The computer memory is filled with a diagnostic program, which is verified in the test set by direct, comparison, then used to test and fault isolate computer circuits. Analog portions of the computer are exercised by digital data from the tape that is converted to analog signals in the test set. Additional tapes may be used to fill the computer memory with operational programs.

(2) *Control-indicator tape.* The control indicator tape provides data that is converted in

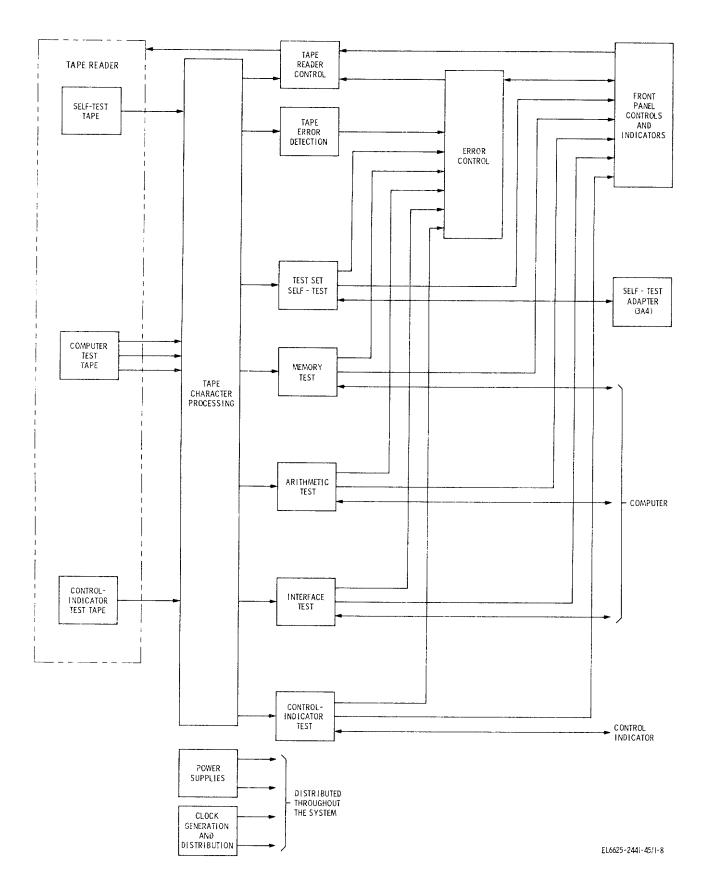


Figure 2-2. Test Set, Navigational Computer-Control Indicator AN/ASM-386, Functional block diagram.

the test set to simulate input and output signals.

The majority of the control-indicator tests require visual monitoring of control-indicator panel indicators and manipulation of control-indicator panel controls. Predetermined data generated by the control-indicator is compared with tape data in the test set. Results of these comparisons are displayed on test set front panel indicators.

(3) *Self-test tape.* The self-test tape thoroughly analyzes the units of the test set.

Data received from the tape reader is applied to the circuits of the test set where it is processed in much the same manner as under actual test operation. This data is then compared with additional tape data and the results are displayed on test set status indicators. Refer to paragraph 2-19 for a detailed description of the self-test tape application.

*d. Power Control.* The test set controls the primary power to the unit under test and the SCU power supply. All voltages generated by the computer or the control-indicator can be monitored by the test set.

#### 2-3. Tape Reader Control

The tape reader is both manually and automatically controlled. Initially, the operator starts the tape reader and can stop it at any time. For a tape-search to a specific major test, the tape reader automatically seeks out the desired number and halts at that number. The location of the desired number, versus the tape location prior to search, has no effect on the ability of the tape reader to locate the number. The tape reader is normally under program control and requires a minimum of operator response after the program has been initiated. The tape reader is automatically controlled during memory fill and verify operation. After its initial start by the operator, the tape reader will automatically fill and rewind, then verify and rewind the operational program tape before halting. The tape reader, while under program control, may be controlled manually. For test set maintenance, the tape reader can be single stepped by using the test panel controls.

#### 2-4. Error Detection and Control

The test set error detection consists of comparing the output of the unit under test against the 2-4 correct

output value provided by the tape. A bit-by-bit comparison takes place; the location of the bits in error are stored in an error register. The contents of this error register are displayed to the operator upon conclusion of the fault analysis. The information displayed on the TEST STATUS REGISTERS display (TM 11-6625-2441-12) is used in conjunction with appropriate maintenance manual for further maintenance instructions. The test set monitors the contents of the error register looking for a non-zero condition. When a 1 appears in the error register, indicating that an error has occurred, the no-go flag (flip-flop) is set. The test set reacts to this no-go state under program control which may or may not halt the fault analysis immediately.

#### 2-5. Error Display

The TEST STATUS REGISTERS display indicates the location of an error in a particular comparison result. Conversion of this error location into a maintenance instruction can be found in the appropriate maintenance manual. The converted information reveals the probable functional area that contains a malfunction.

#### 2-6. Self-Test

Two methods of testing the test set are provided; one method is through the use of a self-test tape that is programmed to exercise all the electronic stages. Another method is the monitoring of key areas of the test set during checkout of the computer or the controlindicator.

a. Programmed Tape, Self-Test. The test set is furnished with a self-test program tape. The tape is used to determine the operational status of the test set. Under the tape program control, the test set analyzes its own outputs, conversion and comparison techniques, and control processes.

b. In-Process Self-Test. The in-process self-tests monitor control and interpretation circuits for disallowed states. Another area of in-process tests monitors the manipulation of data within the test set. Each data word is sensed for saturation to insure that no errors are introduced into the data by the test set. A third form of in-process testing involves the processing of information read from the tape. Here the test set monitors the transfer of data from the tape through horizontal and vertical parity bits, The test set also checks the tape for format errors. Each tape must be generated following a strict set of format rules. The test set checks whether or not the tape has been correctly generated.

## 2-7. Computer Memory Test

An operational tape is used to fill the computer memory with a block of words (1,024 words maximum). The words are read back from memory and compared with the contents of the tape to ascertain the operational validity of the computer memory and the associated electronics. In the process of checking the memory, memory address (NIA) register and memory buffer (MB) register are also checked. A discrepancy in the comparison causes a no-go flag to be set and the fault is displayed on the LCU front panel.

# 2-8. Computer Arithmetic and Control Logic Test

To test the arithmetic and control functions of the computer, data is loaded from the test tape into memory. The data consists of subroutines that test the arithmetic and control logic counters and registers. Two methods are used for detecting malfunctions. One, the computer is programmed to detect errors in the arithmetic and control logic counters and registers. The test set in this case is a passive element only and waits for the computer to indicate an error. The test set is then programmed to perform certain routines to isolate the malfunction to a specific area in the computer. Another method for testing the validity of the computer counters and registers is to load known tape data into an individual or a group of registers, then read and compare the contents of the registers with the known tape data. Any discrepancies in the comparison are displayed on the LCU front panel.

#### 2-9. Computer Interface Test

The computer interfaces with various avionics (platform, control-indicator, etc) in the navigation set. To check the computer's interface operational capabilities, the test set can supply and receive from the computer, signals associated with each avionic equipment under program control. With the test set simulating the avionics, each area of the computer interface is checked out. Input

signals to the computer are the EIP signals, and outputs from the computer are the EOP signals.

a. EIP, EOP Digital Simulation. The test set is capable of simulating all digital inputs required by the computer. The Lest set uses several data registers which, under program control line multiplexing, store the computer digital outputs. The data is then compared with the known correct tape output for fault analysis.

*b. EIP, EOP Analog Simulation.* The procedure for testing the analog circuits in the computer are as follows:

(1) Test signals of known amplitude, both ac and dc, are generated in the test set, and applied to the appropriate input channel of the analog-to-digital converter of the compute,, and the digital output is processed arid compared with the known input. A no-go condition indicates a malfunction in the digital-to-analog converter of the computer with fault isolation to two trays.

(2) Assuming a go condition at (1) above, the digital-to-analog converters in the computer are then addressed to generate an output signal (ac and dc). These signals are properly scaled in the test set and routed back into the computer through the channels previously tested in (1). A no-go at this point indicates a failure in the particular digital-to-analog channel addressed with fault isolation to one tray.

(3) The synchro outputs from the computer are routed to synchro termination networks in the test set in parallel with the synchro inputs to the computer. The synchro output channels of the computer are then addressed to generate an output angle. The sine and cosine outputs from the synchro termination networks are then switched into the ac channel tested in (1), and the output angle verified. A no-go indicates a failure in that particular synchro output channel with fault isolation to one tray.

(4) Assuming a go condition from (3) above, a three-wire synchro signal is applied to the test set and then back through the computer synchro-to-digital channel. A fail to compare in the computer indicates a malfunction in that particular channel of the synchro-to-digital converter with fault isolation to one tray.

#### 2-10. Application of Power

The test set controls not only its own power sequencing but that of the unit under test also. The final turnon control for both the test set and the unit under test (computer or control indicator) is located on the LCU. The computer turnon is interlocked so that computer primary power cannot be turned on until the cooling air blower, located on the computer mounting fixture, is functioning.

#### Section II. DETAIL CIRCUIT ANALYSIS

**2-11. Memory Fill and Verify** (fig. 5-3)

The memory fill and verify test routine exercises the computer memory write and read electronics to determine the functional validity of the memory and its associated controls and registers. Under tape program control, a memory sector (with storage capacity of 1,024 words) is filled with data supplied by the test set tape. The content of the memory is then read back and compared with the original tape data. If no errors exist, the memory is functioning properly. The presence of an error stops the tape and the error is displayed. Interpretation of the display and the necessary corrective action are provided in the appropriate maintenance manual. An overall description of the fill and verify function follow.

a. Memory Fill, General Description. After the front panel switches have been initialized, the tape reader moves to a selected tape address and then continues on to a memory fill (MFIL) instruction. The memory fill instruction is decoded after processing, and the decoded bit initiates control logic for tape movement and memory register loading. The first data from the tape is the memory address, indicating where in memory the first data will be loaded. Tape memory data is loaded into the A-register, and tinder memory fill control shifts the memory address into the computer program counter (CP) register. The A-register is then cleared. The tape follows with a data word, which is stored in the A-register and parallel loaded into the computer memory buffer (MB) register. A clear-write memory cycle is initiated to write the MB register data into the location specified by the CP register. The CP register is then at increment one count, another data word from the tape enters the A-

register and is loaded into the MB register. Another memory cycle is initiated and the data written at the new location specified by the CP register. The CP register is incremented another count. The operation continues until a stop fill instruction is provided by the tape.

b. Memory Verify, General Description. During memory verify, the memory verify instruction is generated, providing a bit for initiating the control logic. Memory verify is initialized when the memory fill instruction has been executed in the auto mode, the end of the tape has been reached, and the MEMORY switch is set to VERIFY. Memory verify is also initialized when in the major mode and memory fill has been executed for the selected major address. Following the memory fill, memory verify is executed for the selected major address. During memory verify, following the loading of the A-register from tape, a read-restore cycle is initiated transferring memory data into the MB register. The contents of MB register are loaded into the test set Bregister and compared to A-register data. Following the compare, a second read-restore is initiated to verify the first read-restore operation. The contents of MB register are loaded into the B-register; a second comparison of A- and B-registers is performed and the results are stored in the C-register, A 1 in the C-register indicates an error for that bit comparison. The C,P register is loaded in the display multiplexer, ready for display as the current memory address. If a failure to compare occurs, the nogo flag is set and the tape stops. If the STOP/RESET push-button is pressed, the C-register is displayed showing the results of the comparison. At any other time, the CP register bits in the display multiplexer are displayed providing a read-out of the faulty memory address. If the comparison is good, the CP register is incremented by one, new data is read into the A-register from tape, and a

new memory word is read and restored from memory to the MB register. The contents of MB register are loaded into the B-register and a comparison of A- and Bregisters performed. The cycle continues until a stop memory fill (SMFL) instruction is encountered.

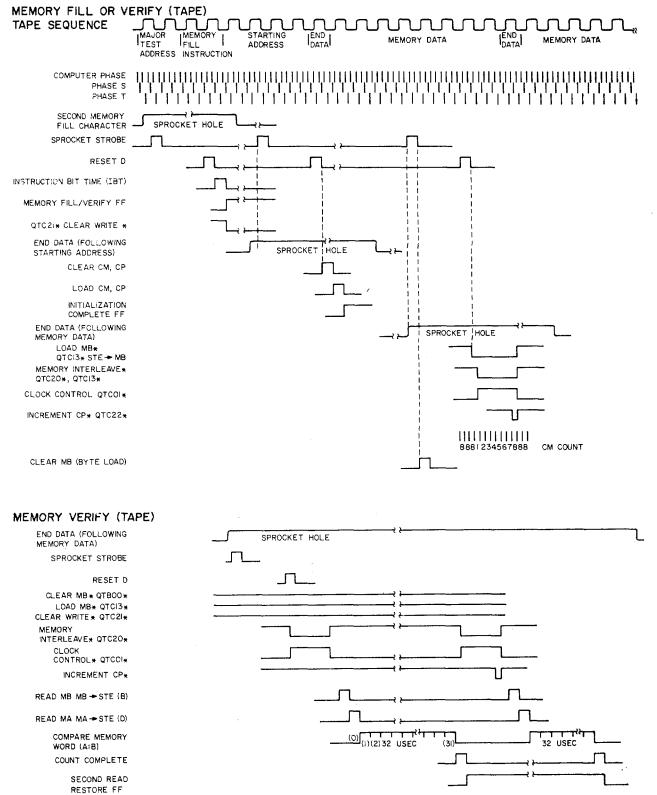
# c. Memory Fill and Verify, Timing Analysis.

The following paragraphs detail the sequential timing analysis of the memory fill and memory verify functions.

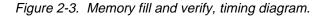
(1) Memory fill, timing analysis. Depending on front panel switch settings, the desired tape address is found either through a tape search, when the MODE switch is at MAJOR or MINOR, or the tape starts at address 00. Following the tape address character, a memory fill instruction character is detected. The second character of the memory fill instruction (fig. 2-3), when entered into the instruction register, is decoded along with the first instruction character to provide the memory fill instruction bit time (IBT). The IBT pulse sets a fill-verify flip-flop indicating a memory fill function and activates the clear-write function of memory. Following the instruction word, the tape provides a data word of four characters that contains the memory start address. Following the start address, an end-of-data character is provided by the tape. The test set senses the end-ofdata character and generates a signal clearing the computer CP register and the memory cycle (CM) register. At the next clock time, the CM register is loaded with a count of 8 to establish the eight-step sequence for loading the memory, and the CP register is loaded with the memory address to provide the computer logic with the first loading address in memory. When CM and CP registers have been loaded, the initialization complete flip-flop is set. The tape puts out a data word consisting of one to seven characters, depending on program design, which is stored in the A-register. An end-of-data character appears at the end of the data word. The control logic generates a load MB pulse when the four data bits of the end-of-data character have been sensed (reset D). Data from the A-register is then loaded into the MB register. A memory interleave pulse and a clock control pulse are generated at the same time, causing the computer to write the contents of the MB register into memory a' the address specified by the CP register. The CM register provides an eight-bit count for the memory-loading procedure. After loading the

memory, the CP register is incremented one count for the new memory address, and the fill instruction cycle starts again. This process continues until a stop memory fill instruction is received. In either case, a verify mode may be entered to verify the data written in memory.

(2) Memory verify, tinning analysis. А memory verify mode results from either of the following conditions. The MODE switch is at AUTO, the MEMORY switch at VERIFY, and memory verify IBT, or the MODE switch is at MAJOR, the MEMORY switch at VERIFY, an>] stop memory fill IBT. In the firs-t condition, the complete tape is read into memory. At the end of the tape, a verify instruction is read forcing the tape to reverse direction to its beginning (address 00) and the verify procedure starts. When the tape reaches the end, a verify instruction is read a second time; the tape again reverses direction to its starting address, but this time the tape movement halts. In the second condition, if the MEMORY switch is set to VERIFY, the fill and verify process will only check the selected major address. After reading and decoding the memory verify instruction, four characters are read from the tape to provide he memory address and are loaded in the CP register. Data characters from the tape are then loaded into the A-register. The end-of-data character (fig. 2-3), due to the verify instruction, will inhibit loading the MB register (QTC13\* true) and inhibit the clear-write command (QTC21\*), providing a read-restore memory command to the computer. A memory interleave and a clock control pulse initiate the read-restore memory function by loading the memory data into the MB register. The CP register is not incremented at this time because two read-restore and compare cycles are completed for each memory data word. On the second read and compare, the CP register is incremented. When the read MB and read MA/ pulses are generated, data from MB register is shifted into the B-register and the MA register data shifted into the display multiplexer of the test set. The data stored in A-register is compared with the data stored in B-register on a bit-by-bit basis and the results are stored in the C-register. If comparison is good, the whole procedure of read-restore and compare is repeated for the new memory address stored in the incremented CP register. This process is continued until a stop memory fill instruction is decoded. If a compare error is sensed, a tape stops and the memory



EL6625-2441-45/1~14



address is displayed; pushing the STOP/RESET button displays the C-register, showing which bit failed. During a memory verify cycle, an error could be a result of either an incorrect memory verify or an incorrect test instruction result both results are displayed.

d. Worst Case Fill and Verify, Timing Analysis (fig. 2-4). The worst case memory fill and verify check is performed when the computer test tape is mounted in the tape reader. An instruction, load and verify worst case memory test, is decoded generating an IBT pulse which sets the worst case memory test (WCMT) flip-flop. After the second instruction character from tape, the memory starting address from tape is placed in the Aregister. An end-of-data strobe occurs at the end of the memory address. The CM and CP registers are cleared, and at the next clock pulse, the CP register is loaded with the contents of the A-register (memory address) and the CM register is loaded with a count of 8 in preparation for a memory cycle. Initialization is now complete. The worst case memory data word is then read from tape and stored in the A-register. The worst case memory data word is programmed as an alternating 1-0 pattern. Following the end-of-data character, the tape reader is stopped and not used again until the worst case memory test is concluded. The A-register data is loaded into the MB register and the clear-write operation proceeds in the same manner as described in b above. On the next memory write cycle, instead of new data being read from tape, the A-register is right shifted (end around) one bit to provide new data contents to the A-register. A clearwrite cycle is initiated and the new data is stored in memory and the new incremented CP address. Similar operations continue until the ten low-order bits of the CP register are saturated signifying that a 1,024-word sector in memory has been loaded. A saturated CP register (count of 1023) will set up the memory verify mode. Verification of the loaded data now begins. The CP register is cleared (CP = 0) and the clear-write flip-flop (QTC21\*) is set indicating a read-restore command. Read MB and read MA pulses are generated shifting the MB register contents into the B-register and the MA contents to the display multiplexer. The A- and Bregisters are compared. A second read-restore cycle is initiated to check the first restore and is then followed by a compare. If any compare fails, the no-go flag is set and remains set. Following the two comparisons, the CP register is incremented one count by resetting QTC22\*

for one clock period. The A-register is shifted right one bit and a verify cycle is started once again. The cyclic action continues until the CP counter reads 1023. During this cycle when the second read and compare has been established, the CP register is incremented to 0, worst case mode test flip-flop reset (the end worst case test flip-flop had been set during CP = 1023 and reset during CP = 0), and a restart tape reader pulse generated. The tape reader is restarted and the program checks, via a branch instruction, whether the no-go flag was set.

e. Single Load and Single Read Memory, Timing Analysis. The program provides the capability of either writing a single word in memory from A-register (SLMA) or from the C-register (SLMC). The program also provides the capability for reading out a single word from memory (SREM) at the specified address. Procedural steps for accomplishing a single loading are the same as for a fill cycle except the tape halts after the first word has been written in memory (fig. 2-5). To write in memory from the A-register, the SLMA instruction causes the memory address to be loaded into CP register. Simultaneously, the CM register is filled with a count of 8 in preparation for a memory cycle. A second operand (following the memory address) may follow. In any case, whether the A-register is loaded from tape or not, and end-of-data bit following the second data word will initiate loading of the MB register from the A-register. A clear-write cycle is initiated by memory interleave (QTC20\*) and clock run (QTCO1\*) to write the data into memory location specified by the CP register. The CP register is incremented completing the cycle. For writing in memory from the C-register, the SLMC instruction causes the memory address to be loaded in the Aregister and then in the CP register. Simultaneously, the CM register is loaded with an 8 in preparation for a memory cycle. Following end-of-data character for the memory address, the data word from tape is loaded into the C-register. A second end-of-data character loads the data from C-register to the MB register. A clear-write memory cycle is initiated to write the data into the memory location specified by the CP register. An SREM instruction is initiated when the instruction is sensed and decoded. The memory address is loaded into A-register. When the first end-of-data character occurs, CP and CM registers

#### TM 11-6625-2441-45-1

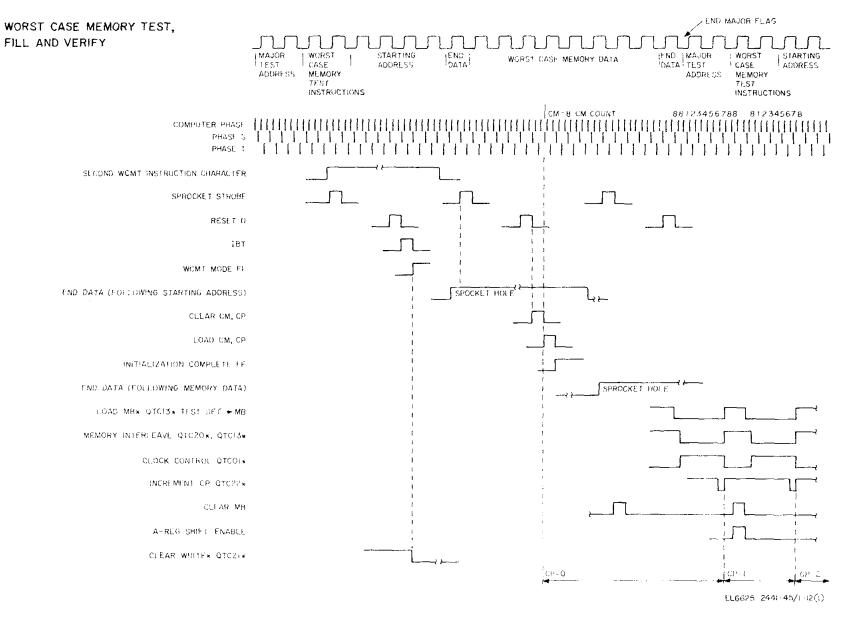


Figure 2-4 (1). Worst case memory fill and verify, timing diagram (part 1 of 3).

#### WORST CASE MEMORY TEST, FILL AND VERIFY

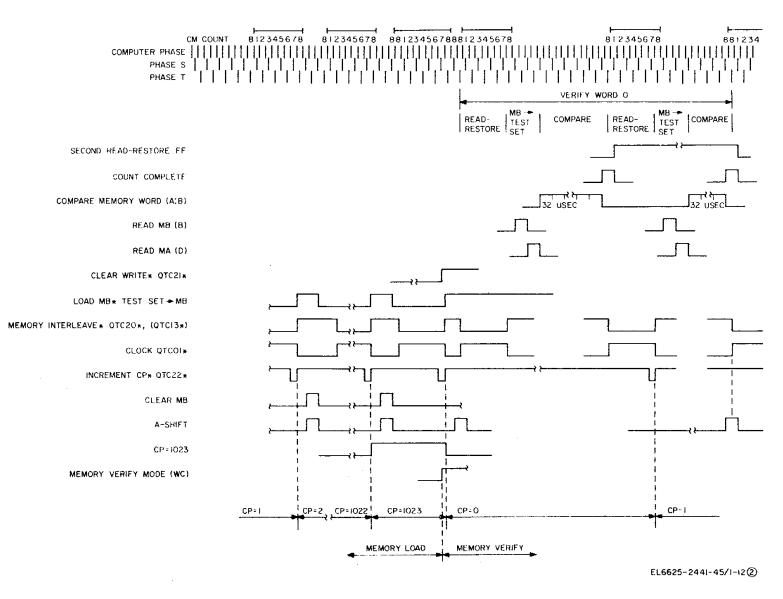


Figure 2-4 (2). Worst case memory fill and verify, timing diagram (part 2 of 3).

WORST CASE MEMORY TEST, FILL AND VERIFY

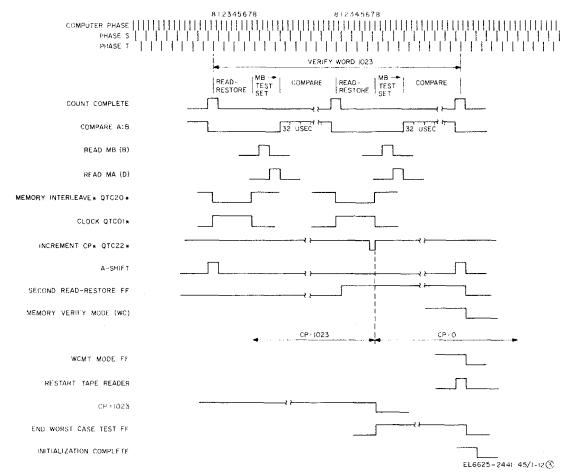
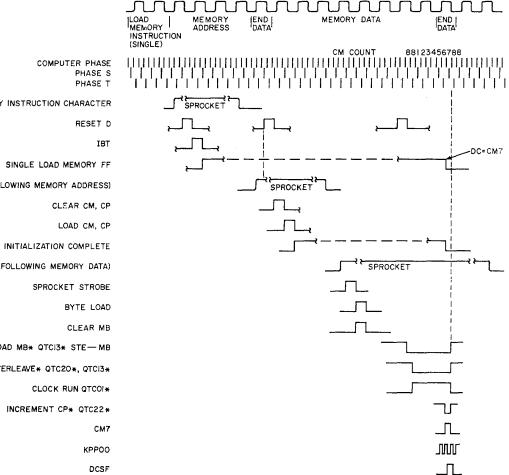


Figure 2-4 (3). Worst case memory fill and verify, timing diagram (part 3 of 3).

2-12

#### SINGLE LOAD MEMORY INSTRUCTION



COMPUTER PHASE PHASE S

SECOND LOAD MEMORY INSTRUCTION CHARACTER

SINGLE LOAD MEMORY FF

END DATA (FOLLOWING MEMORY ADDRESS)

END DATA (FOLLOWING MEMORY DATA)

SPROCKET STROBE

CLEAR MB

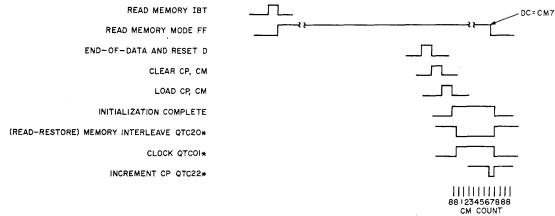
LOAD MB\* QTCI3\* STE- MB

INTERLEAVE\* QTC20\*, QTCI3\*

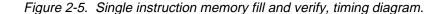
CLOCK RUN QTCOI\*

INCREMENT CP+ QTC22+

#### SINGLE READ MEMORY INSTRUCTION



EL6625-2441-45/1-13



are cleared, and on the next clock pulse CP register is loaded from the A-register and CM register filled with a count of 8. A read-restore signal and a clock pulse initialize the read-restore cycle, and the memory data from the address specified in the CP register is loaded into the MB register. The CP register is incremented one bit, completing the cycle.

#### 2-12. Load and Read-Compare

(fig. 2-6 and 5-4)

The program provides for loading computer registers, either in groups or individually, with tape data to check

the operational validity of specific registers. A readcompare instruction allows the contents of the selected computer register to be read and compared with the tape data. bit by bit. Any discrepancy in the compare generates a no-go flag and provides a display of the malfunctioning bit. The following subparagraphs describe the load and read-compare functions for the registers.

**a. Load.** Loading word no. 1 into the computer causes a particular routine to be performed, and the resultant output to be applied to the test set. Word no. 1 consists of the data loaded into

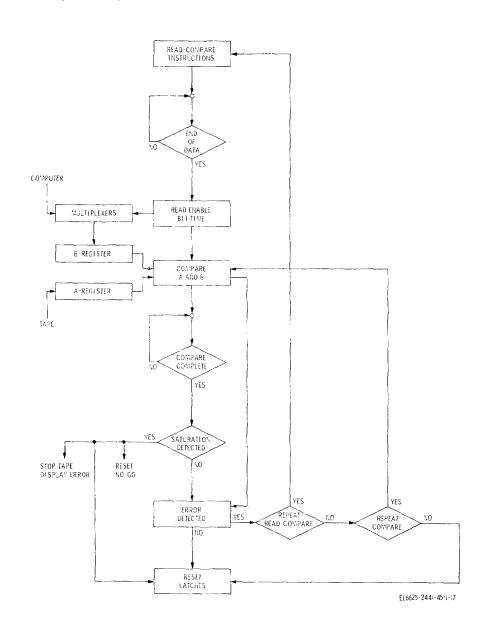


Figure 2-6. Read-compare program, flow chart.

the CA, CE, CI, and CP computer registers. These registers can be loaded in parallel or individually, depending on the data to be provided by the computer. Additional logic is provided for loading the CM and MB These registers can only be loaded registers. individually. Loading the MB register can be controlled by an instruction word, or the memory fill and verify operation (refer to para 2-11). This capability requires an MB register control logic circuit, through which the enable signals are applied. Logic is also provided to load and read-compare an additional computer memory unit (XMB), if a second memory unit should be installed. Loading is initiated by enabling the load control logic with an instruction word. The A-register is loaded with data from the program tape and the computer registers are cleared, enabling the drivers to load the selected computer register or registers with the contents of the Aregister.

(1) The load control logic receives an instruction from the tape control and processing logic (para 2-20), to load either CA, CE, CI, CP, CM, NIB, XMB, or word no. 1. The load logic activated by this

PHASE S CLOCK

instruction is latched (fig. 2-7). The logic senses the presence or absence of the first data character from the tape. If tape data is present, the A-register is cleared and loaded with data from the tape. if tape data is not present, the existing A-register data is utilized.

(2) Control bits received from the tape control and processing logic, enables the register and A-register; clock signal. Data from the tape is loaded into the Aregister in byte serial form, consisting of 1 to 7 bytes, depending on which computer register or registers have been selected. The contents of the A-register are parallel shifted to all computer register Livers through the register output multiplexer.

(3) Following the data word that loaded the Aregister, an end-of-data pulse is applied to the load control logic. This causes a clear pulse to be applied to the computer, clearing the selected register or registers and enabling the driver logic for the selected register or registers. The enabled driver logic loads the data in the respective computer register, and the load latch logic is reset.

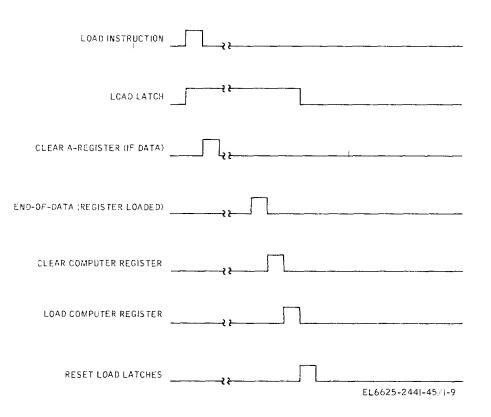


Figure 2-7. Computer register loading, timing diagram.

b. Read-compare. A read-compare instruction causes loading of computer data into the B- register and comparison with data in the A- register (fig. 2-7). The results of the comparison are applied to the C-register (fig. 2-8). If there is an error in the comparison, an automatic self-test routine is performed within the test set to determine whether the failure is due to a malfunction in the computer or the test set. Read-compare is initiated by enabling the read-compare logic with an instruction word. The A-register is loaded with data from the tape and the B-register loaded from the computer; the A- and B-registers are bit shifted to the comparator and the results of the comparison are stored in the C-register.

(1) The read-compare logic receives an instruction from the tape control and processing logic to read-compare a particular computer register or word. The read-compare logic activated by this instruction is latched. The logic senses the presence or absence of the first data character of' the tape. If tape data is present, the A-register is; cleared and loaded with tape data. If tape data is, not present, the existing A-register data is, utilized.

(2) Data is loaded into the A-register in the same manner as in a(2) above. The data conlsists3 of 1 to 7 bytes, depending on the register or word selected.

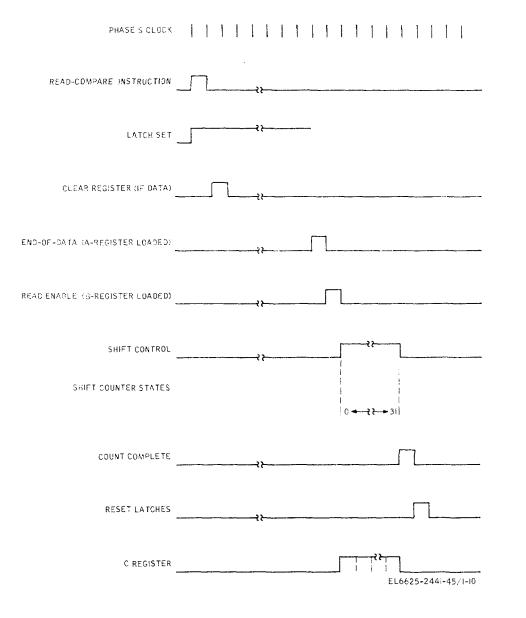


Figure 2-8. Read-compare, timing diagram.

(3) Following the data word that loaded the Aregister, an end-of-data pulse is applied to the readcompare control logic. This enables the input multiplexer, the register input multiplexer, and the shift control logic. The B-register is loaded, and the shift control logic applies a clock signal to the A-, B-, and Cregisters. Data is always present at the input multiplexer. Only the multiplexer enable signals are needed to initiate loading of the B-register.

(4) The contents of the A- and B-registers are bit serially shifted into the comparator logic. The content of each bit location of the A-register is compared with the content of the same bit location in the B-register; the result is shifted into the C-register. At the end of the comparison operation, a count complete pulse is generated and the latches reset. The A- and B-registers are continually checked for saturation (all I's). Saturation of either or both the A- and B-registers indicates that a flip-flop in the saturated TM 11-6625-2441-45-1 register has malfunctioned. If this condition exists the latches are reset, the test set malfunction light is on1, and the tape is stopped.

*c.* Read-Compare Reiteration (fig. 2-9). Any comparison failure causes the error control to apply a signal to the read-compare control logic. To ascertain the existence of an error, the entire read-compare routine is then repeated. If the failure persists, the error control causes only the compare function to be repeated. If the failure is still evident, a branch on no-go instruction causes various routines to be performed within the computer, to further isolate the fault.

**2-13. Branch Control Function** (fig. 2-10)

The branch function provides for branching to a specific address and continuing the program with

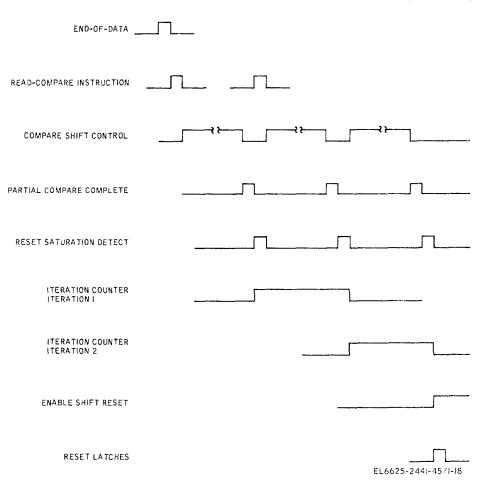


Figure 2-9. Read-compare reiteration, timing diagram.

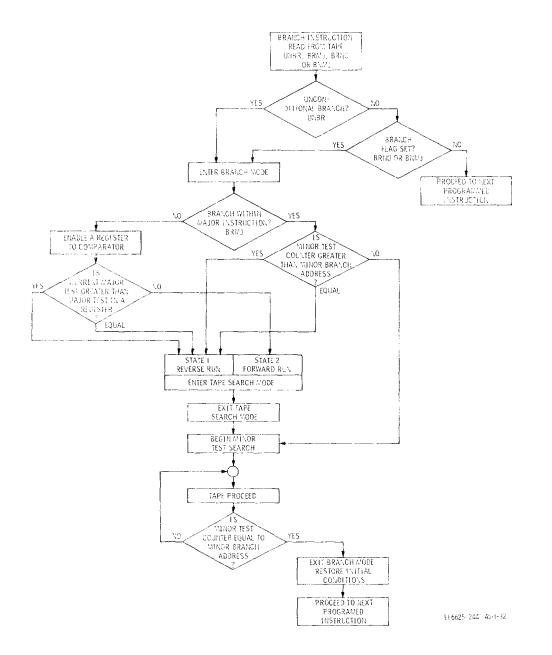


Figure 2-10. Branch control function, flow chart.

the instruction stored at that address. A branch function is initiated by one of four tape instructions: unconditional branch (UNBR), branch on major mode (BRMJ), branch on no-go flag (BRNO), and branch on no-go flag when within a major mode (BRMJ).

a. Unconditional Branch. An unconditional branch instruction read from the tape causes the logic to enter the branch mode. Data from the tape following the branch instruction consists of major and minor test numbers to which a branch is desired. The data is loaded into bits 17 through 32 of the A-register. The

minor test number occupies the low-order bits (17 through 24) and the major test number is stored in bits 25 through 32. A comparison is then made between the major test number stored in the A-register and the major test number currently displayed. The result of the comparison causes the tape to run forward or reverse (tape search mode) so the tape search logic can make a comparison between the current major test number and the desired major test number. If the major test number [n the A-register is greater than the current major test number, the tape reader runs forward; if less, the tape reader reverses. During tape search, the tape always runs at high speed. Refer to paragraph 2-20 for a detailed description of the tape search function. After a comparison has been made, the tape search mode is terminated and the test set remains in the branch mode. The minor test search is entered and the tape runs forward at low speed. In a minor test search, the tape always runs forward because the search always starts at address 00. In a minor test search, all instructions are inhibited except increment minor test counter (INCM). A comparison of the minor test counter contents and the minor test number stored in A-register continues until a comparison is achieved. The branch mode is then terminated and normal instruction execution follows.

b. Branch on Major Mode. A branch on major mode instruction provides for branching only to a desired minor test and assumes that the major test in the Aregister is the current one. The instruction causes the test set to enter the branch mode. Following the instruction, tape data provides the minor test number which is stored in the A-register as the desired minor test. Tape search mode is entered when a comparison is made between the A-register minor test number and the minor test counter contents. The A-register is gated to the tape search logic in the branch mode. If the Aregister minor test is less than the current minor test, the tape moves in a reverse direction. However, if the desired minor test is greater than the current minor test, tape search is not entered; minor test search routine is entered. The tape continues to run forward at low speed until a comparison is detected by the logic.

*c.* Branch on No-Go. A branch instruction can be executed if a no-go flag is set, indicating an error has been detected. After reading the branch instruction and identifying the set side of the no-go flag, the procedure for the branch and tape search function is the same as described in a above.

*d.* Branch on No-Go Within Major. A branch instruction can be executed if a no-go flag has been set during a major mode of operation. The procedures outlined in b above are applicable for this operation after the logic has detected a no-go in a major mode.

**2-14. Computer and Control-indicator Interface Test** Logic is provided within the test set for simulating the input-output units associated with the computer. Logic is also provided for processing analog signals, and for simulating the computer when the control-indicator is being tested.

a. Analog Processing. To check the computer reception and processing of analog signals, test signals of known amplitude are generated within the test set. These signals (ac and dc) are applied to the appropriate inputchannels of the computer analog-to -digital converters, and compared with the known input. Digitalto-analog converters in the computer are then addressed to generate an analog signal. Analog signals from the computer are divided into three groups; synchro, voltage, and low-level signals. The analog control word (instructions from tape reader) enables one of these signals to be scaled within the test set, and routed back into the computer, via the analog channels previously tested. If the analog control word selects a synchro signal, that signal is routed directly back to the computer. These signals are also processed by the test set. to provide sine and cosine signals. The sine and cosine signals are applied to the computer for angle verification. All signals applied to the computer analog input channels can also be applied to the TEST position of the VOLTAGE MONJTOR switch on the SCU. This capability is controlled by the analog control word.

(1) Computer analog channel test (fig. 2-11). a load analog control word instruction is received. the contents of the A-register (analog control word) are loaded into the B-register. This analog control word causes ac and dc test signals to be applied to a MOS switch, and the MOS switch control to activate the appropriate MOS switch. This condition causes the selected test signal to be applied through the buffer amplifier to the computer analog input channel.

(2) *Synchro and voltage signals* (fig. 2-12). Computer synchro output signals are received by the test set and applied directly back to the computer synchro-to-digital converters, via synchro input channels. These signals are also applied to the synchro termination networks within the test set, which output the sine and

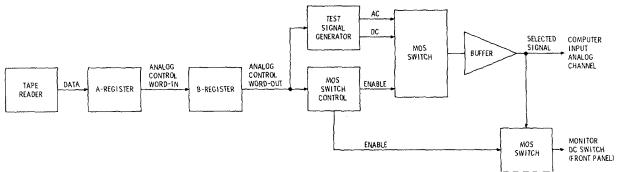


Figure 2-11. Analog processing test, data flow block diagram.

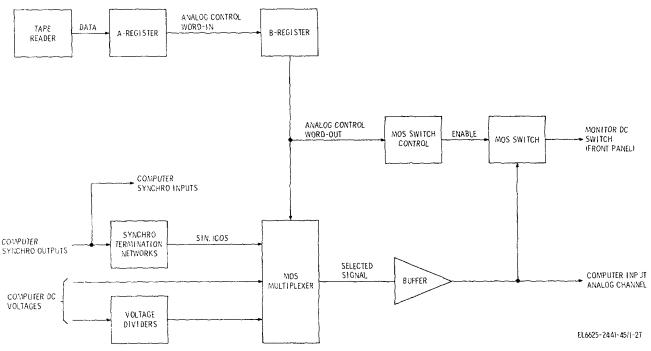


Figure 2-12. Analog processing – synchro voltage signals, data flow block diagram

cosine function of each synchro. The sine and cosine signals are applied to the MOS multiplexer, causing the signal selected by the analog control word to be applied through the buffer amplifier to the computer analog input channel. To insure the computer has provided the voltages required for a second memory unit, a voltage divider network receives the voltages and establishes a signal at a nominal level. This signal is applied to the MOS multiplexer and processed in the same manner as the synchro signals, when selected by the analog control word. Test set voltages are received and processed in the same manner. The following chart lists the synchros

and voltages tested, and the analog control word construction for each synchro and voltage.

(3) Low level signals (fig. 2-13). Low level analog signals from the computer are applied to the MOS switches. Depending on the construction of the analog control word, the MOS switch control enables one of the switches, causing the selected signal to be applied to the preamplifier. The amplified signal is applied through another MOS switch (enabled by the same analog control

Synchros and voltages	chros and voltages Description Analog control word															
-,		1	2	3	4	5	6	7	8	9	10	11	12	13	14	15
True airspeed feedback	Sin	0	0	0	x	x	x	x	x	x	0	0	0	1	0	0
	Cos	0	0	0	x	x	x	x	x	x	1	0	0	1	0	0
Magnetic heading-course indicator	Sin	0	0	0	x	x	x	x	x	x	0	1	0	1	0	0
	Cos	0	0	0	x	x	x	x	x	x	1	1	0	1	0	0
Bearing minus heading	Sin	0	0	0	x	x	x	x	x	x	0	0	1	1	0	0
	Cos	0	0	0	x	x	x	x	x	x	1	0	1	1	0	0
Range to destination (units)	Sin	0	0	0	x	x	x	x	x	x	0	1	1	1	0	0
	Cos	0	0	0	x	x	x	x	x	x	1	1	1	1	0	0
Magnetic heading-BDIII	Sin	0	0	0	x	x	x	x	x	x	0	0	0	0	1	0
	Cos	0	0	0	x	x	x	x	x	x	1	0	0	0	1	0
Range to destination (tens)	Sin	0	0	0	x	x	x	x	x	x	0	1	0	0	1	0
	Cos	0	0	0	x	x	x	x	x	x	1	1	0	0	1	0
Magnetic heading-TACAN	Sin	0	0	0	x	x	x	x	x	x	0	0	1	0	1	0
	Cos	0	0	0	x	x	x	x	x	x	1	0	1	0	1	0
Range to destination	Sin	0	0	0	x	x	x	x	x	x	0	1	1	0	1	0
(hundreds)	Cos	0	0	0	x	x	x	x	x	x	1	1	1	0	1	0
Computer																
+30V +30V +12V -6V +12V -6V +5V +5V		0 0 0 0 0 0 0	0 0 0 0 0 0 0	0 0 0 0 0 0 0	x x x x x x x x	x x x x x x x x	x x x x x x x x	x x x x x x x x x	x x x x x x x x	x x x x x x x x x	0 1 0 1 0 1 0	0 0 1 1 0 0 1	0 0 0 1 1 1	0 0 0 0 0 0 0	0 0 0 0 0 0 0	1 1 1 1 1 1
Test set																
+15V		0	1	0	0	0	0	0	0	1	x	x	x	0	0	0
26 Vac		0	0	1	0	0	0	0	0	1	x	x	x	0	0	0

word), and is processed in the same manner as the synchros and voltages. The following 'chart lists the lowlevel signals tested, and the analog control word construction for each signal. *b. Load Discrete Word* (fig. 2-14). Data in the discrete input holding register is loaded into the computer upon receipt of a load discrete word instruction. The holding register can be

Low-level signals						An	alog	cont	rol w	ord														
	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15									
Drift angle error	1	0	0	1	0	0	0	0	х	х	х	х	0	0	0									
Lateral steering error	1	0	0	0	1	0	0	0	х	х	х	х	0	0	0									
Groundspeed error	1	0	0	0	0	1	0	0	х	х	х	х	0	0	0									
Deviation	1	0	0	0	0	0	1	0	х	х	х	х	0	0	0									
Azimuth cage error	1	0	0	0	0	0	0	1	х	х	х	х	0	0	0									

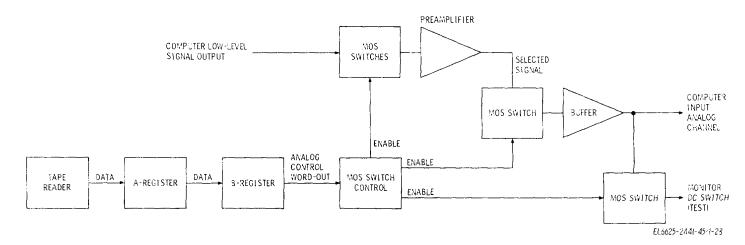


Figure 2-13. Analog processing—low level signals, data flow block diagram.

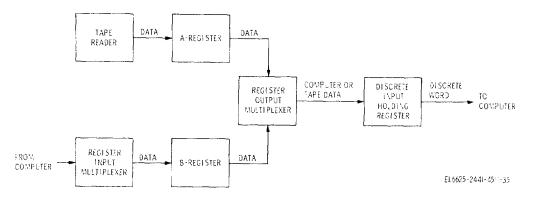


Figure 2-14. Load discrete word, data flow block diagram.

loaded with data from either the A- or B-registers, depending on the load instruction. The A-register receives data from the program tape and the B-register from the computer. Both groups of data are applied through the register output multiplexer. If the B-register is used, it is loaded by an instruction preceding the load discrete word instruction.

*c.* Discrete Terminations. Portions of the discrete output word (from computer) are analog signals. During a read-compare discrete output word instruction, these

analog signals must be converted to digital form to be processed by the test set. This operation is performed by the discrete input termination network. The entire discrete word is then read and compared as described in paragraph 2-12.

*d.* Control-Indicator and TACANT Interface (fig. 2-15). Depending on the operation being performed by the computer, control indicator, or TACAN, data and data control pulses are received from the computer. Data

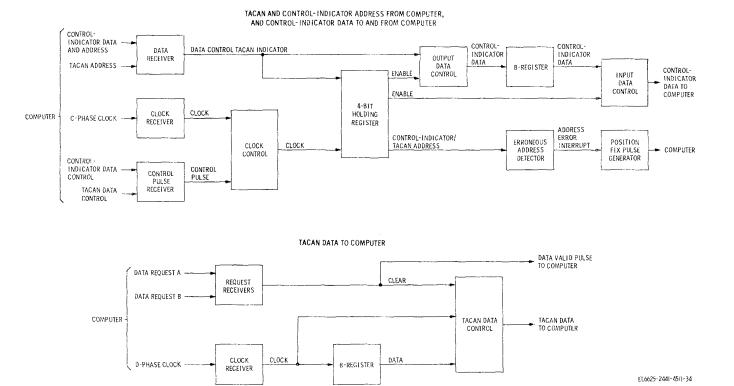


Figure 2-15. TACAN and control-indicator data processing, data flow block diagram. 2-23

is applied to the output data control logic, and the four-bit holding register. When the control pulse is high, a clock signal causes the four-bit register to be loaded (representing control-indicator or TACAN address). When the control pulse goes low, the clock signal is inhibited and the four-bit register stops shifting; the erogenous address detector decodes three bits of the register, and checks for a valid address. If the address is not valid, a posse fix signal is generated and applied to the computer, causing the computer to perform a subroutine. The fourth bit of the four-bit register is used only when processing control-indicator data, and causes the data word received from the computer to be loaded into the B-register, or the contents of the B-register to be applied to the computer (representing a controlindicator data work to computer). Logic is provided for applying TACAN data to the computer when TACAN data has been requested by the computer (fig. 2-16). Two data request signals (A and B) are generated by the computer and applied to the test set, causing a data valid pulse to be applied back to the computer. The data valid pule also clears the TACAN data control logic. The contents of the B-register ae then applied to the computer (representing a TACAN data word) at the rate of the phase D clock, also generated in the computer.

e. Control-indicator Position Fix Test (fig.2-17). Pressing the POS. -FIX push-button on the controlindicator, causes a pulse t be applied to logic to check the pulse width. A 2-MHz clock

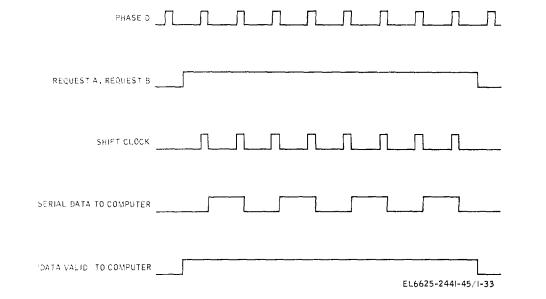


Figure 2-16. TACAN data to compare, timing diagram.

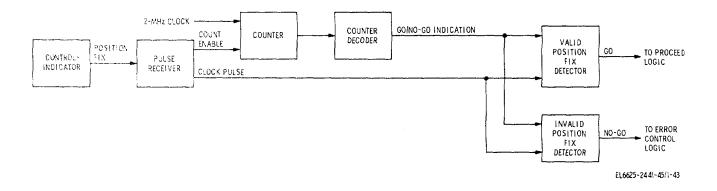


Figure 2-17. Control-indictor position fix test d flow block diagram.

signal drives a counter, which is decoded and applied to the detector logic. The position fix signal is also applied to the detectors, and depending on the state of the counter, the time period of the position fix pulse is determined. If the pulse width is less than 4 microseconds or greater than 8, an error signal is applied to the error detection logic, causing a no-go condition. If the pulse width is within the 4- to 8-microsecond range, a signal is applied to the tape proceed logic, causing the tape to drive.

# f. Control-Indicator MODE Switch Test (fig.

2-18). To test the control-indicator MODE switch, an instruction causes a latch to set. This condition enables the MODE switch position drivers, and applies a ground signal to the wiper of the switch. Positions of the switch can now be applied, through the display multiplexer, to the front panel REGISTERS display indicators. The nine MSD of the REGISTERS display indicator, correspond to the nine positions of the switch.

Each position of the switch causes an 8 to be displayed in its respective display.

*g.* Control-indicator Input Test (fig. 2-19). An instruction to load the control indicator causes the tape reader to load 32 bits of data (data word) into the A-register, and then into the control-indicator. A clock signal and a control pulse are also applied to the control indicator. The control pulse is high for the first, four bits of the data word (control-indicator address), then low for 28 bits.

*h.* Control-Indicator- Input-Output Test (fig. 2-20). To check the input-output capabilities of the control-indicator, an instruction causes the clock signal and control pulse to be applied to the control-indicator in the same manner as for the control-indicator input test. Four data bits (representing control-indicator address) are loaded into the A-register from the tape reader, and then shifted to the control-indicator. Depending on the address, the control-indicator either

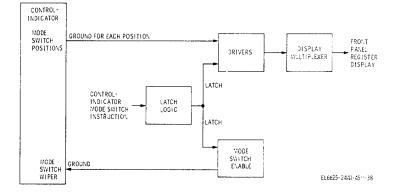


Figure 2-18. Control-indicator MODE switch test, data flow block diagram.

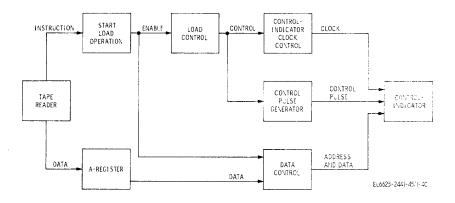


Figure 2-19. Control-indicator input test, data flow block diagram.

shifts data into the B-register, or the contents of the I;register are shifted to the control-indicator.

*i.* Platform Interface Tests (fig. 2-21). Three tests are performed to check the platform interface logic. Each of the three instructions (one per test) causes a latch to set, and reset at the completion of the test. These latches set up initial conditions within the test set, for that particular test.

(1.) The first test insures that the proper incremental platform angles have been developed by iH3le computer. An instruction causes one of four data words (torque inputs) to be applied to the up/down counter, through the torque input control logic. The counter shifts at a 6.25-kHz rate, and counts up when the torque input is ground. After 11 milliseconds, the computer applies a signal that Stops the 6.25-kHz clock when the torque input goes high. The contents of the counter are then loaded into the B-register. An acknowledge signal is then applied to the computer, followed by the contents of the B-register. This process is repeated for tie remain i31g three data words.

(2') The second test verifies the capability of the computer to count increment velocity pulses, the test set generates four different pulse trains in two directions, off two axes. One of seven eight-bit data control words is loaded into the B-register from the computer. The computer applies a signal to reset and start the

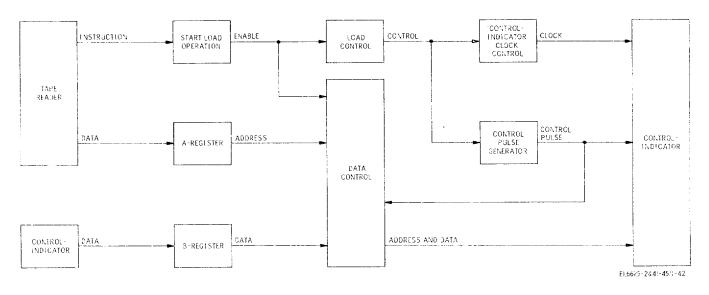


Figure 2-20. Control-indicator input-output test, data flow block diagram.

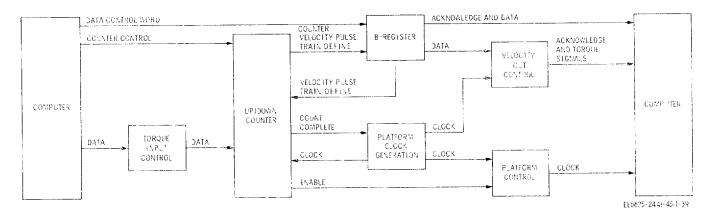


Figure 2-21. Platform interface test, data block diagram.

up/down counter, and applies the platform 100-kHz clock to the test set. The time duration of the velocity pulse train is defined by the contents of the B-register. When the up/down counter completes a count, the clock is stopped and an acknowledge signal is applied to the computer. This condition causes the computer to perform a subroutine, comparing the torque rate with time duration of the counter. This procedure is repeated for the remaining six data control words.

(3) The third test provides for a self-test of the computer interface. The computer applies torquing signals to the test set, enabling logic for receiving incremental platform angle signals. The platform clock signal is then enabled, and the up/down counter reset and started. After 1.3 seconds, the counter is loaded into the B-register, then sent to the computer for comparison with known results.

#### 2-15. Front Panel Indicators and Error Control (fig. 2-22)

Indicators on the test set front panel indicate the unit under test, the go/no-go status of the unit or test set, that power is applied to unit and test set, and memory fill and verify operation is being performed.

a. Setting the UNIT switch to ON enables the computer and control-indicator define logic, and causes the UNIT indicator to light. The unit being tested causes +5 V7 signal to enable the corresponding define logic. The test tape for each unit applies a signal that identifies itself, to the define logic enabled by the unit being tested, and causes the respective indicator (NCU, CIU, or SELF TEST) to light. If the wrong tape has been inserted, or a unit has not been connected to the test set, the indicators flash and the tape stops.

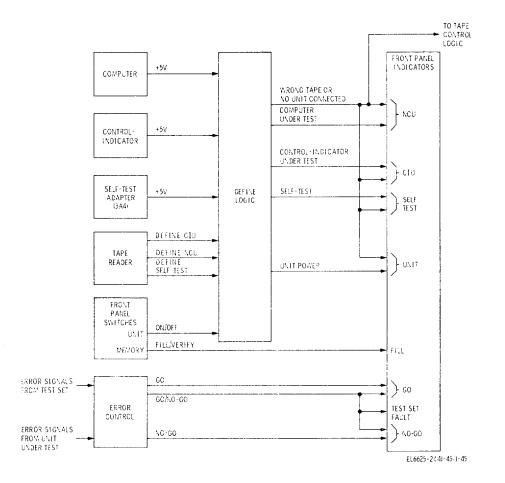


Figure 2-22. Front panel indicators and error control, data flow chart.

b. The FILL indicator lights when the memory fill/verify operation is being performed.

c. The results of the in-process test (within the test set) and error signals from the unit under test are applied to the error control logic, indicating a go or no-go condition. Error signals from the in-process tests have precedence over error signals from the unit under test. If the test S(et is in the go condition, the go and no-go logic for the unit being tested is enabled. The GO indicator is lit during testing and goes out at the end of tape; if an error has been detected, the GO indicator )., goes out and the NO GO indicator lights. In a test set failure, the GO and NO GO indicators are inhibited and the TEST SET FAULT indicator lights.

#### 2-16. Clock Generator

The test set generates clock signals either in sync with the computer clocks, when testing the computer, or selfgenerates clock signals when testing the controlindicator or self-testing. a. Clock Generation During Computer Checkout. A 2-MHz clock signal (KPPOO) is received from the computer (fig. 2-23) and inverted by the test set logic (XKAOO1). Signal XKNAOO1 is delayed by 65 nano-seconds (XKA002) and XKAOO1 is also applied to a countdown synchronized flip-flop whose output provides a I-Miz clock signal, KKAOO5. Gated logic generates phase S and phase T negative-going 1-MIJz clocks for distribution throughout the test set.

(1) The computer 2-MHz square wave clock is checked continuously for correct phase shift limits to the 4-MHz square wave generated by the test set. Circuits provided by the test set compare the phase relationship of the two frequencies during a specified time period. If the two signals are beyond the designated limits, an error signal is generated. Figure 2-24 is a timing diagram showing the comparison period of the two frequencies. Each frequency is applied to a special coded counter. The 4-MHz test period occurs during the count of 3; the 2-MIIz test period

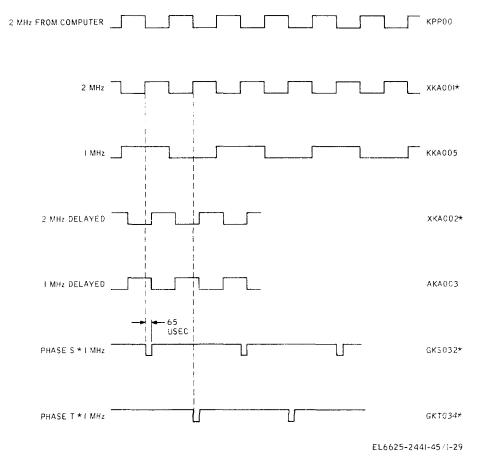


Figure 2-23. Test set clock system with computer clock running, timing diagram.

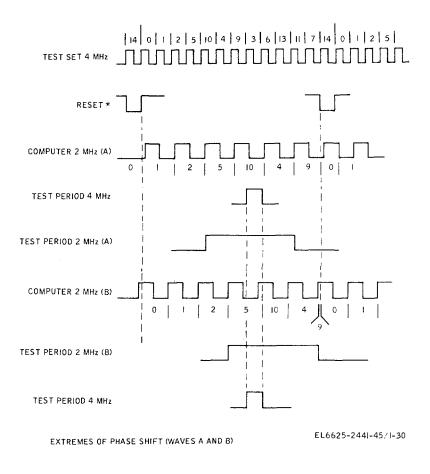


Figure 2-24. Two-MHZ-clock square wave, timing diagram.

occurs during the counts of 5, 10, and 4. The two test period signals are applied to an AND gate. If the output of the AND gate is low, the phase relationship is within limits. If the gated output is high for four consecutive comparisons, an error signal is generated indicating an out-of-phase condition.

(2) Three instructions control the computer clock. A run computer clock instruction (RCPC) causes the computer clock to be turned on for an indefinite period. The clock may be stopped by either the computer program or by an instruction from the test set tape (STCL). The computer clock can also be programmed to run for a specified number of clock periods by a run clock conditional instruction (RCNC). This instruction causes the computer clock to be turned on for N clocks (1 through 999), if a memory cycle does not occur during the last seven clocks. If a memory cycle is begun during the last seven counts of N, the clocks are stopped immediately and the memory cycle counter is cleared. When an unconditional clock run instruction is performed (RCNU), the clock runs continuously. The clock will be turned on for exactly N clocks (1 through 999).

Clock Generation During Self-Test and b. Control-Indicator Checkout. Clock pulses for self-test and control-indicator checkout are derived from the test set clock-generating circuits. A 4-MHz oscillator output applied to three countdown flip-flops (fig. 2-25) provides the 500 kHz necessary for self-test and control-indicator operation. Through logic gating, phase S and phase T clocks (0.5 MHz) are generated and distributed throughout the test set. Timing signal phase C is used for communication with the control indicator unit. To simulate computer clocks when in the self-test mode and enable the computer clock mode, signals GTTOOO\* and GKAO41\* are generated. GTTOOO\* is connected back through the self-test adapter into QUPOOO, simulating KPPOO, 2-MHz square wave from the computer. Phase S and phase T in this mode are 1-MHz clocks.

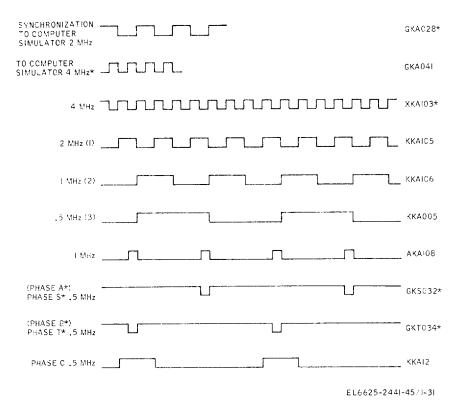


Figure 2-25. Clock generation during self- it and control-indicator checkout, timing diagram.

# 2-17. Power Supply 2AIPS1 (fig. 5-5)

The test set power supply is housed in the SCU. 'the following sub-paragraphs describe the power supply circuits, generation of de power supply voltages, and the power supply protective circuits.

*a. Power supply control* circuits. The power supply control circuits consist of transformer TI, -4.7 regulator VR1, relays K1 and K2, and power sequence switching assembly A2.

(1) The power supply is prepared for turnon when primary C-phase power is applied through connector J1-VWv' to the primary winding of transformer T1 The Output of the secondary winding of T1 is rectified by diodes CR1 and CR2 to provide +28 V auxiliary. The secondary winding center tap of T'1 is connected to power ground to provide the +28 V auxiliary ground return. The +28 V auxiliary is filtered by capacitors C6, C7 and C8 and supplied to relays K1 and K2, +4.7 V regulator VR1, power sequence switching assembly A2, negative voltage crowbar A3, positive voltage crowbar A44, and connector J1-N and Z. Regulator VR1 provides +4.7 V auxiliary to connector J1-M.

(2) The power supply is turned on in two steps. Power ground is applied to the ac power on signal line through connector J1-c to power sequence switching assembly A2, pin 2. A2 applies a ground through FL3 to relay K1 operates and closes the 115-V, 400-Hz threephase power leads from connector J1-J, H, and G to the primary windings of A1T2. Dc voltages from rectifier assemblies A1Z1 through A1Z4 are applied to the inputs of regulators VR2, VR3, VR4, VR6, VR, 7, and VR8. The regulator control circuits are turned off by resistance divider networks connected through the contacts of dc power relay K2 to ground. The +28 V auxiliary is then applied to the dc power on signal line through connector J1-b to A2, pin 18. A2 applies a ground through F14 to relav K2. K2 operates and removes the resistance divider networks from ground, and regulators VR2, VR3, VR4, VR6, VR7, and VR8 turn on the dc voltages.

(3) When A2 receives a crowbar signal from the negative voltage crowbar A3, positive voltage crowbar A4, or +5 V crowbar A7, relay K2 is deenergized and initiates de power shutdown. A ground signal is generated which lights the appropriate indicator on the SCU test panel (fig. 2-26). When A2 receives a no-go signal from the voltage monitor A5S relay K2 is deenergized initiating dc power shutdown. A ground signal is generated which lights the OUT TOL indicator on the SCT test panel. The OVERRIDE switches (rig. 5-5) apply the override signal to A2 which causes relay f'2 to energize, removing the ground signals from the SCU test panel indicators. The OVERRIDE switches are used only during maintenance operation.

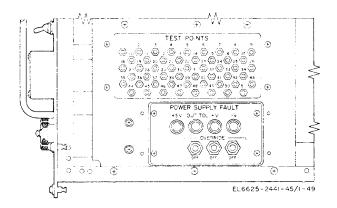


Figure 2-26. Test panel, Signal Conditioning Unit TS -2913/ASMJ-386.

Generation of -25 V. +28 V. and ±15 V. b. The output of the high-voltage secondary windings of transformer A1T2 is connected to rectifier assemblies AIZI and A1Z2. The secondary winding center taps are connected to ground return. The outputs of A1Z1 and A1Z2 are in parallel and provide negative and positive power supply voltages. The negative voltage is connected through LC filter (L1, C1I) to regulators VR2 and VR3. The outputs of VR2 and VR3, regulated -25 V and -15 V respectively, are connected through FL5 and FL6 to negative voltage crowbar A3, voltage monitor AS, and connector J2. The positive voltage is connected through LC filter (L2, C12) to regulators VR4 and VR6. The outputs of VR4 and VR6, regulated +28 V and +153 V respectively, are connected through FL7 and FL9 to the positive voltage crowbar A4, voltage monitor A5, and connector J2. The output of VR4 is also connected through diode A6CR4 to override the +28 V auxiliary.

Generation of +5 V and +4.7 V. The output С. of the low-voltage secondary windings of transformer A1T2 is connected to rectifier assemblies A1Z3 and A1Z4. The secondary winding center taps are connected to ground return. The outputs of AiZ3 and A1Z4 are in parallel to provide a positive power supply voltage. The positive voltage is connected through LC filter (1L3, C13) to +5 V regulator VR7 at VR7L1-6 and +4.7 V regulator VRS. The current path through VR7 is from the +22 V input through an input filter (VR7L1 pin 6 to pin 5 and capacitors VR7C1, VR7C2, and VR7C3), a power switch circuit (VR7QI, VR7Q2, VR7R1, and VR7R2), an output inductor (VR71, 1 pins 1 and 2 to pins 3 and 4). and current-sensing resistors (VR7RCS and VR, 7R4) to the +5 V output. The output voltage of VR7 is compared with an internal reference voltage set by potentiometer VR7Ai-Ri3. While the output voltage is low, the power switch circuit is conducting (on state), current flow through the output inductor increases, and the output rises. When the output exceeds the reference level sensed by the voltage loop comparator, the level shift switch circuit causes the power switch circuit to cut off (open state). Simultaneously, the feed-back reduces the reference voltage level slightly. When the power switch circuit is in the open state, the self-induced voltage of the output inductor causes current to flow through diode VR7CR1, the output inductor, and the current-sensing resistors to the output. This current will decrease, and as it falls below the level demanded by the load, the output voltage will begin to decrease. As the output voltage drops below the reduced reference voltage level, the voltage-loop comparator circuit causes the level shift switch circuit to set the power switch circuit to the on state. The output voltage is thus regulated to an average level equal to the average level of the reference voltage. The small feedback signal applied to the reference voltage accelerates the switching speed, reducing switching losses. The output inductor and the switch timing capacitors, with the resultant output ripple, control the switching rate of the regulator. The current-loop comparator circuit causes the level shift switch circuit to set the power switch circuit to the open state when the voltage drop across the current-sensing resistors, caused by the load current, exceeds the internal reference level. When the load current has decreased, the current-loop comparator circuit causes the level shift switch circuit to set the

power switch to the on state. Since the rate of load current change is limited by the output inductor, the switching rate is set to a safe maximum value. The output of VR7, regulated +5 V, is connected through FL8, FL10, and FL11 to the +5 V crowbar A7, voltage monitor A5, +5 V bus W1 and connector J2. The output of VR8, regulated +4.7 V, is connected through FL12 to the voltage monitor AS, positive voltage crowbar A4, and connectors J1 and J2.

d. Voltage adjust controls. The voltage adjust controls (potentiometers) located in the building block voltage regulators (BBR) are listed in the following chart

Protective circuits. The protective e. circuits in the power supply comprise negative voltage crowbar A3, positive voltage crowbar A4, +5 V

Nomenclature	Reference designators	Regulated outputs	Control	Value (ohms)
()		+28 V	R14	500
BBR (I) BBR (III) BBR (IV)	VR4 V, R6	+15 V	R14	500
BBR (IV) BBR (V)	VR2 VR3 VR1A	-25 V -15 V	R14	500
DDR (V)	VR8	Aux. + 4.7	VR13	500
Switching regulatorVR7		+ 4.7 V	VICIO	000
		/		

2-18. Power Control and Distribution (fig. 5-6)

Three-phase 115-Vac, 400-Hz and +28 V primary power is required to operate the test set. Power is applied to the SCU and then distributed to the LCU and units to be series tested through а of connectors and interconnecting cables.

Power Control. Three-phase 115 Vac is а. applied to SCU PRIMARY POWER circuit breaker CB4 through P'RINIARY POWER 115 Vac 400 Hz 3 PH connector Ji and RFI filter FL1. Plus 28 V is applied to NCU POWER 28 VDC circuit breaker CB2 and CIU POWER 28 VDC circuit CB3 through PRIMARY POWER 28 VDC connector J2 and RFI filter FL2.

(1) *Primary power* on. The test set is prepared for use by operating PRIMARY POWER

crowbar A7, and voltage monitor A5. The crowbar circuits monitor the regulated dc voltages and protect the test set from excessively high output voltages. If any of the power supply voltages exceed a specified limit, the crowbar connects that output to ground through silicon controlled rectifier (scr). The scr for crowbars A3 and A4 are contained within the sealed unlit and QT is the scr for crowbar A7. The output of the crowbars are applied to power sequence switching circuit A2 to light the appropriate POWER SUPPLY FAULT indicator on the SCU test panel. When the scr is operated by an over voltage condition, the resultant ground connection is sensed by the voltage monitor circuit A5. The function of the voltage monitor is to convert any loss of voltage or excessively low-voltage condition into a no-go signal. This signal 's applied to the power sequence switching circuit, deenergizing relays KT and K2, and the power supply is shut down.

+28 V	R14	500
+15 V	R14	500
-25 V -15 V	R14	500
Aux. + 4.7 + 4.7 V	VR13	500
501/		0000

+ 5.9 V VR7A1R13 2000

circuit breaker CB4. Circuit breaker CB4 applies threephase 115 Vac to power supply PS1. The C-phase line turns on SCU blowers BT, B2, and B3, and lights POWER PRIMARY indicator DS5. The A-phase line is connected to NCU POWER 115 VAC 400 Hz circuit breaker CB1. The B-phase line is connected to LOGIC CONTROL UNIT connector J5-E and through interconnecting cable, to SIGNAL CONDITIONING UNIT connector J3-E to operate LCU blowers BT and B2. Circuit breaker CB1 applies the A-phase line to NAV COMPUTER UNIT BLOWER connector J10-A and the primary of transformer T1 supplies 26 V rms, 400 Hz to the NAV COMPUTER UNIT connector J9 and to card cage assembly A3. Circuit breaker CBE also closes the circuit to NCU POWER 115 VAC 400 Hz indicator DST.

(2) Plus 28 V on. Operating NCU POWER 28 VDC circuit breaker CB2 applies +28 V to NAV COMPUTER UNIT connector J9 and lights the NCU POWER 28 VDC indicator DS2. Operating CIU POWER 28 VDC circuit breaker CB3 lights the CIU POWER 28 VDC indicator DS3 and applies +28 V to LOGIC CONTROL UNIT connector J5 and through interconnecting cable, to SIGNAL CONDITIONING UNIT connector J3.

Power Distribution. Power supply PS1 is b. prepared for turn on by operating POWER AC switch S3. A ground is connected to the ac power on signal. POWER AC indicator DS4 and NCU POWER 115 VAC 400 Hz indicator DS1 light from +4.7 V auxiliary. POWER ELAPSED TIME mete M1 operates from +28 V auxiliary. The +28 V auxiliary is also sent to LOGIC CONTROL UNIT connector J5-X and through interconnecting cable, to SIGNAL CONDITIONING UNIT connector J3-X. Operating the LCU POWER TEST SET switch S7 applies +28 V auxiliary to operate LCU POWER ELAPSED TIME mete M1 and return the dc power on signal to SIGNAL CONDITIONING UNIT connector J3-W, and through interconnecting cable, to LOGIC CONTROL UNIT connector J5-W. The dc power on signal turns on power supply

PS1.

*(1) Plus* 5 V. SCU bus W3 distributes +5 V to card cage assemblies AI, A2, and A3, VOLTAGE MONITOR switch S1, LOGIC CONTROL UNIT

to SIGNAL CONDITIONING UNIT connector J3. LCU bus W3 distributes +5 V to card cage assemblies AI, A2, A3, and A4, test panel A6, and TEST POINTS 88, 93 and 98.

(2) Minus 15 V. SCU PS1 supplies -15 V to card cage assembly A3 and to VOLTAGE MONITOR switch S1.

(3) Plus 4.7 V. SCU PSI supplies +4.7 V through TB1 to VOLTAGE MONITOR switch S1, to LOGIC CONTROL UNIT connector J5 and, through interconnecting cable, to SIGNAL CONDITIONING UNIT connector J3. LCU bus W4C distributes +4.7 V to card cage assemblies AI and A4 and to LAMP TEST switch S8.

(4) Plus 15 V. SCU PS1 supplies +15 V to card cage assembly A3, VOLTAGE MONITOR switch S1, LOGIC CONTROL UNIT connector J4 and, through interconnecting cable, to SIGNAL CONDITIONING UNIT connector J5. Connector J5 connects +15 V to LCU card cage assembly A2.

(5) Minus 25 V. SCU PS1 supplies -25 V to card cage assembly A3 and to VOLTAGE MONITOR switch S1.

(6) Plus 25 V. SCU PS1 supplies +25 V to VOLTAGE MONITOR switch SI.

(7) Plus 28 V. SCU PS1 supplies +28 V to card cage assembly A3 and to VOLTAGE MONITOR switch S1.

# Section III. TAPE FORMAT AND CONTROL

#### 2-19. Self-Test Tape Operation

a. General Description. The self-test tape is run first to insure that the test set is operating properly. During self-test, the test set analyzes its own outputs, conversions and comparison techniques, and control processes. If the self-test tape completes its run without detecting a failure, the computer or control-indicator test tape is loaded. If a fault is detected while running the self-test tape, the tape stops; the test set displays inform the operator of the fault by displaying a particular number. The operator consults the troubleshooting charts for an interpretation of the displayed number. (1) The test set contains internally mounted controls to assist maintenance personnel in manual isolation of malfunctions of the test set. Test set power and supply failures can be overridden so that the failure can be rapidly ascertained. The internal controls are inhibited when the test set is performing a unit test routine.

(2) When a test set fault is located, the faulty card is replaced with a new one.

(3) Self-test checkout by tape program incorporates two forms of testing, semiautomatic and automatic. Semiautomatic checkout verifies operation of functions which require operator observation. This checkout is also used to expand the fault isolation capability of the test set. Areas tested in the semiautomatic checkout are instruction decodes, inprocess fault detection, branching, tape format, register operation, analog/ synchro channels and control, memory verify functions, control-indicator pos fix test circuits, EOP tape control, and panel display functions.

Automatic checkout provides a thorough and detailed exercise of all areas of the tst set under various conditions of discrete inputs, outputs, and logic inputs/outputs.

b. Semiautomatic Checkout. The first portion of the tape program is the Initial confidence test. This test checks such circuits a power or reset, pull-up voltages, clock, tape data, and so forth. After each test the tape stops, and the operator checks for normal front panel indications. If the indications are normal, the START push-button switch is pressed and the operation is repeated until the final test ha been completed. If, at any time during the performance of the initial confidence check, a malfunction is detected, the operator refers to the related troubleshooting chart for recommended repair procedures. The remainder of the semiautomatic checkout is contained in major tests 1 through 19 on the program tape. These test are used to isolate faults in the test set which are not detected by the automatic portion of the self-test. Tests in this portion of the checkout are similar to those in the initial confidence test and are functionally grouped into major tests.

c. Automatic Checkout Upon completion of the confidence tests, the tape program provides an automatic check of the test set logic circuits. Automatic checks include the signal flow through discrete termination cards. All logic circuits are tested by programmed instruction signals.

d. Self-Test Instruction Initialization of various tests are controlled by the following instructions.

(1) Instruction TST1. Instruction requires the loading of up to 40 bits of self-test data into self-test registers located in the LCU and SCU. Self-test bits are assigned functions which, in general, control data paths. Following the loading of the self-test register, a number of data paths have been closed, the net effect being that some data (registers or test points) will be present at the parallel inputs of the B-register. A clock strobe is generated, loading the -register with whatever data is present and entry clearing the self-test register. The Bregister is then compared with the expected results stored in the A-register through a compare instruction.

(2) Instruction TST2. A more extensive self-test is performed with this instruction. Up to 40 bits of self-test data are loaded into the self-test register. Self-test bits are assigned functions which, in general, control data paths.

Following the loading of the self-test register, a number of data paths will be closed, the net effect being that some data (registers and test points) may be present at the parallel inputs of the B-register. However, the selftest bits may also control logic not directly concerned with loading data into the B-register. Assuming that the Bregister is to be loaded, the loading takes place by a non-self-test instruction. In self-test 2 (TST2), the performance of certain regular instructions will cause data to appear at the inputs of the B-register, and will also initiate a load strobe to clock the B-register. The self-test register is then entirely cleared by the strobe. The B-register is compared with the expected results stored in the A-register by a compare instruction.

With instruction TST2, logic operations that do not require loading the B-register in parallel, may be controlled or simulated. In this case, a load strobe is not generated. Following whatever logic operation has been performed, the B-register will in general be loaded serially. The B-register is compared with the expected results by a compare instruction.

(3) Instruction TST3. The primary function of this instruction is to test the self-test register. The operand following the instruction consist of 72 bits arranged as 18 data characters. Data is loaded byte serially into the self-test register and the A-register simultaneously. After eight byte the A-register is loaded. However, shifting into the registers continue, with the least significant data being lost in the A-register. After shifting of the 10th byte, the self-test register is completely loaded. Beginning with the 11th byte, the output of the A-register and self-test register are compared, by an exclusive OR gate, bit serially. If a bit fails to compare, the TEST SET FAULT indicator lights, the tape reader stops, and the REGISTERS display shows the internal error register by a numeric readout. The readout is then interpreted by referring to the troubleshooting charts to isolate the malfunctioning card in the self-test register.

(4) Instructions GSP3. This instruction verifies the gyro stabilized platform logic circuits located in the test set. When instruction GSP3 is used, the 100 k11z is checked, and the dynamic velocity pulse train generator is checked. During the test, the input/output complete line is checked to verify that the pulse occurs at the right time.

# 2-20. Tape Control and Processing (fig. 5-7)

This logic provides for three functions; controlling the tape reader (TR), processing tape characters, and checking each tape character for

errors. Controls *on* the front panel of internal test panel, or an instruction from the program *tape*, determine the direction and speed of the TR. The tape error detection performs various checks of' each tape character and group of characters (word) to insure the validity of the data from the TR. The tape character processing logic receives a Lest address (TA) instruction or data word, and processes the word accordingly.

a. Tape format. A tape character consists of one group of eight punched holes (bit positions) on the program tape. Tape characters are used to construct four types of program words. Bits 5 and 6 of each character define the type of word. The following chart illustrates the status of bits 5 and 6, and the number of tape characters for each program word.

Program word	Status of bits 5 and 6	Number of tape characters
Test address	56	2
Instruction	5- 6	2
Data	5- 6	1 to 7
End-of-data	5- 6	1

The tape is programmed to provide the words in the following sequence: test address, instruction, data, and end-of-data. Checks are performed, during running of the tape, to insure the correct tape format. Bits 1 through 4 comprise the data portion of a pure binary character; bit 7 is used for a code delete; and bit X is the parity bit used to cause odd parity within a character. If the

total number of bits used in a character equals all even number (i.e., 4), bit 8 is pinched. The data portion of a character is utilized in constructing a word. The first character represents the last significant digit (LSD), and the following characters build up to the most significant digit (MSD) of the word. An illustration of the construction of a test address word follows.

		MSD	LSD	
	Bit 1	0	0	
	Bit 2	0	0	
Data portion	Bit 3	0	0	
			Sprocket hole	
	Bit 4	0	0	
Test	Bit 5	0	0	
address code	Bit 6	0	0 Tape directio	n
	Bit 7	0	0	
	Bit 8	0	0	

Tape Reader Control. The TR can run b. forward, or reverse, at high or low speed. This capability is controlled by the TR control logic. The LCU front panel START push-button, in conjunction with the MODE switch, is used to start the tape. Depending on the position of the MODE switch (AUTO. MAJOR, or MINOR) at initialization, the TR either proceeds for-ward at low speed or begins a tape search operation. The AUTO position causes the entire test tape to be processed. The MAJOR and MINOR positions cause a tape search operation (for the selected major test) to be performed. During tape search. the TR is driven in the necessary direction and at the required speed, until the tape TA number equals the major test number selected on the front panel TEST NUMBER, /MAJOR SELECT thumbwheel (TW). That test (major) or tests (minor) are then performed. A tape search operation is also initiated upon receipt of a branch instruction from the tape (para 2-13). A sprocket strobe is generated in the TR control logic. During maintenance operations, logic is provided for controlling the TR from the internal test panel also.

(1) Auto mode. Auto mode control logic enables tape run control logic, which provides input, control signals to the TR. Pressing the START pushbutton, causes a proceed signal to be applied to logic enabled by the auto mode coontlol. The tape run control provides the necessary signals for the TR to run forward at low speed(TEST NUMBER/MAJOR SELECT) thumbwheel are inhibited during auto mode). The TR is now under control of the program tape and runs as directed.

(2) Major mode. Front panel TEST N[NII3ER/MIAJOR thumbwheel (TW) were used to manually select, the desired major test. Pressing the START push-button initiates a tape search operation. When the TA selected is higher than, the TA at which the tape is stopped, the T. will advance at high speed and overshoot the selected TA by approximately 5 inches of tape. The tape drive then reverses automatically, drives at high speed, and again overshoots the selected. TA by approximately 5 inches. The tape drive' advance-s the tape at low speed to the selected TA and he tape stops (fig. 2-27). If the T.A selected by the TW is less than the TA at which the tape is stopped, the TR will run in reverse at high speed, overshoot the selected TA by approximately 5

inches of tape, then run forward at low speed and stop at the selected TA.

*Example*: The test tape is stopped at TA = 40 and the selected address is TW = 50, the TR will advance at high speed and stop approximately 5 inches past TA = 50. The tape drive will reverse and rewind approximately 10 inches of test tape and stop. The tape drive will then advance at low speed until TW = TA = 50. If TA = 30 and TW = 20, the TR will run at high speed and reverse (rewind) and stop approximately 5 inches past TA = 20. The tape drive will then advance the test tape at low speed until TW = TA = 20.

The contents of the TA register represent the program tape major test number (BCD). The TW and TA numbers are compared to determine whether the TW number is less than, greater than, or equal to the TA number. If the TW number is greater than the TA number when the tape search start signal is received, the run and forward flip-flops are set (fig. 2-28). This condition causes the TR to run forward at high speed (phase 1). After receiving the next TA word, the TW and TA comparator is enabled. If the TW number is still greater, phase 1 continues. Due to the high speed of the TR, an overshoot occurs when a TW = TA (TR ready line) condition is detected. When the next TA number is received, the compare result strobe resets the forward flip-flop, causing high-speed reverse (phase 2) to be initiated. The overshoot recurs when a TW = TAcondition is detected a second time (reverse run), and sets the forward and low flip-flops initiating low-speed forward (phase 3). When the TW = TA condition is detected a third time, the tape search flip-flop is reset; the TR stops.

Pressing the START push-button causes the selected major test to be performed. The TR stops at the completion of the test. Pressing the START push-button again, causes the tape search and test operation to be repeated. If a different test number has not been entered via the TW, the same major test is performed. If the tape search was initiated by a branch instruction, the tape search continues until the tape-selected minor test is located (refer to (3) below).

(3) Minor mode. With the MODE switch set to MINOR, pressing the START push-button, and then the STOP/RESET push-button, causes a tape search operation to be performed as in the major mode. At completion of the tape search operation, the first minor test (00) of the selected

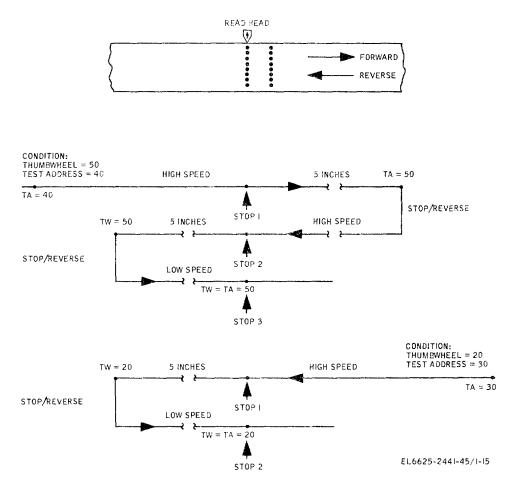


Figure 2-27. Tape direction, flow diagram.

major test (TW selected) is performed. The tape is stopped at the completion of the test, and the next minor test is initiated by pressing the START push-button. This action is continued until the last minor test has been completed. Pressing the START push-button, after completion of the last minor test, advances the tape to the next major test and at the completion of minor test 00, the tape stops.

(4) Sprocket strobe generation. Each time a sprocket hole is detected, the TR applies a signal to the tape control logic. A pulse is generated and used as a timing signal by the tape control and processing logic.

c. Tape Error Detection. li-process error checks are performed on each tape character received by the test set to insure the accuracy of each character read and transmitted by the TR. Tests performed check the horizontal and vertical parity, seventh-hole condition, format, buffer register, and tape character counter. (1) *Horizontal parity check.* This test is performed to check whether the total number of bits used in each character is an odd number. Signals representing each bit of a character are received from the buffer logic and decoded to determine the total number of bits. If the total equals an even number, a nogo signal is applied to the error detection logic.

(2) Vertical parity check. An instruction to perform a vertical parity check is periodically received by the test set. This test verifies that the correct amount of bits have been processed over an extended period of time. The location of the instruction on the program tape is determined by the programmer. The instruction sets up control logic to test the state of the vertical parity register. The seven active tape bits (1, 2, 3, 4, 5, 6, and 8) cause their respective flip-flops to toggle, when that bit position is punched. The programmer decides what additional tape characters are required to put the flipflops in the reset state.

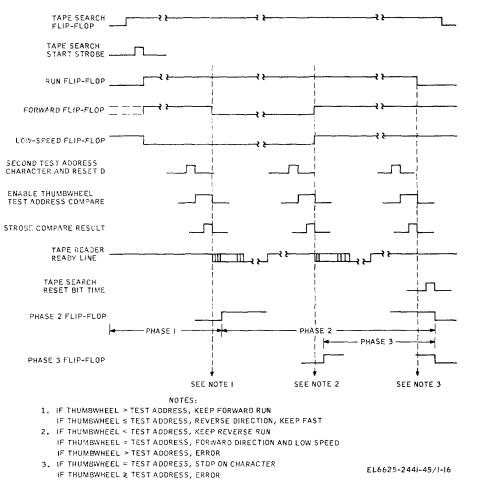


Figure 2-28. Tape search, timing diagram.

(3) Seventh-hole check. Logic is provided to detect a punched seventh-hole condition, which indicates an optional code delete.

(4) Tape format cheek. The tape format logic receives tape data (bits 5 and 6) and determines the type of word (TA, instruction, data, or end-of-data) to be processed. After the type of word has been determined, related logic in the tape processing logic is enabled. Format checks are made to insure the correct amount of characters in program words (fig. 2-29).

(5) Buffer register error check. This check is performed to determine whether the buffer register is functioning properly. Timing signals are received from the byte shift register, which causes bits 1 through 4 from the tape to be compared with the same bits as they are serially shifted out of the buffer register. For example, if the LSB loaded into buffer register is high, the first bit (LSB) shifted out is high. A comparison failure indicates a buffer register malfunction and causes the TEST SET FAULT indicator to light.

(6) Tape character counter. A tape character counter is provided to check the quantity of characters in a minor test. This counter is incremented one count by the instruction bit time (IBT) and counts to a maximum of 1, 023. Completing a 1, 023 count indicates that an error exists and causes the TEST SET FAULT indicator to light. The counter is reset at the

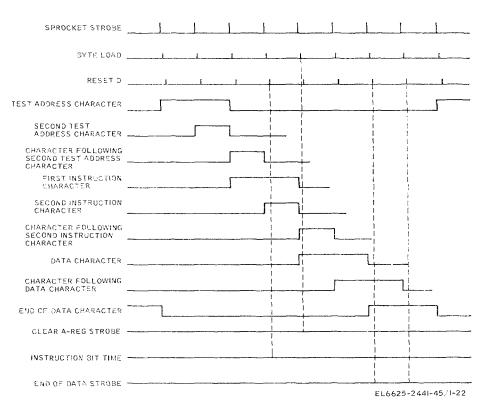


Figure 2-29. Typical tape format check, timing diagram.

beginning of each minor test by the increment minor test counter instruction.

d. Tape Character Processing. Program words are received by the buffer logic and applied to logic pertaining to that type of word. TA words are applied' trough the TA register to the TR control logic, to be used during tape search operation. TA words are also applied to the test set front panel,: displaying the major test being performed. An instruction word is applied' through 'the 'instruction' register, td the instruction decoder, minor test' counter tape character. counter, and the stop control. A data word is applied directly from the buffer logic to the A-register.

(1). Buffer logic.: The buffer logic receives parallel data from the TR. Additional logic- is provided receive data from the internal test panel, and to display that data during maintenance operations. The buffer logic applies the data to the error de6ction logic, and to the TA and instruction registers and the A-register. Depending on which register has been enabled by the tape format logic, the data is processed accordingly.

(2) Byte shift register (fig. 2-30). The byte shift register enables the sifting of the buffer, TA

and interaction register. and the A-register, and controls the buffer register error check: The byte shift register contains four flip-flops (A, B, C; and D), and functions as a counter. At detection of a sprocket hole, the sprocket strobe causes the D-fib-flop to set for six phase S clock pulses. During this time, : A-, B-, and Cfib-flops set at each consecutive phase S clock pulse, then reset consecutively. The byte load pulse is generated when A-flip-flop sets, enabling the buffer register to be parallel loaded with data from the, tape. When the B-flip-flops sets, the shift four bits signal enables the buffer register to serially shift its contents into the TA or instruction registers or the A-register, and the buffer register error logic. At the sixth phase, clock pulse, the

PHASE S CLOCK

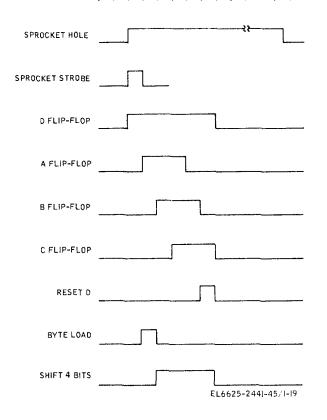


Figure 2-30. Byte shift register, timing diagram.

D-flip-flop and the shift four bits signal are reset by the reset D signal. Data cannot be loaded into the buffer register until the next sprocket hole detection (next character).

(3) TA register (fig. 2-31). Bits 5 and 6 (both true) of the TA word enable the TA register. Bits 1 through 4 of the tape character containing the LSD of the TA word, are parallel loaded into the buffer register. The buffer register serially shifts its contents to the LSD portion of the TA register, LSB first. When the second TA character is received, it is serially shifted into the MSD portion, MSB last. The contents of the TA register now comprise two BCD numbers which are converted, displayed on the front panel, and applied to the comparator logic (for tape search operation).

(4) *Instructions register* (fig. 2-32). Upon completion of a TA word processing, bits 5 (true) and 6 (false) enable the instruction register. Bits 1 through 4 of the first instruction character are parallel loaded into the buffer register, then serially shifted into the instruction register, LSB first. Bits 1 through 4 of the second character are serially shifted into the instruction register, iNSB last. The contents of the instruction register are decoded, and the instruction is processed. The following chart illustrates the octal number, code, and function of each instruction.

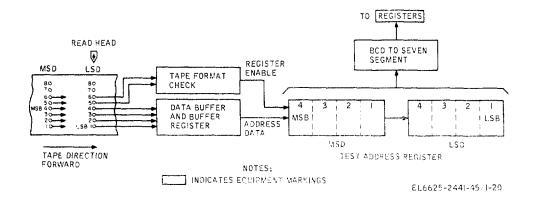
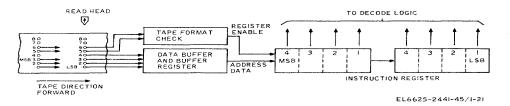
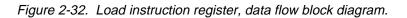


Figure 2-31. Load test address register, data flow, block diagram.





Octal no.	Code	Function
000	General NOPE	Causes no test operation to occur. Used to cycle test set through instruction decode with- out a NCU/CIU test operation.
016	NOOP	Causes no test operation to occur. Used to cycle test set through instruction decode with- out a NCU/CIU test operation.
154	DNCU	Causes a latch to be set, which is AND-gated with the computer-power-on to energize the status indicator NCU. DNCU latch, with DCIU and DSTS latches, perform error check-ing to insure that the proper tape (computer, control-indicator, or self-test) is on the tape reader when the proper device is connected (computer, control-indicator, or self-test adapter) to the test set.
155 DCIU		Causes a latch to be set, which is AND-gated with the control-indicator-power-on to energize- the status indicator CIU, Error checking as in DNCU.
156 DSTS		Causes a latch to be set, which is AND-gated with the self-test-adapter-connected to energize- the status indicator SELF TEST. Error checking as in DNCU.
112 EOTF		Causes a flip-flop to be set, which inhibits any forward-run command to the tape reader. (EOTF flip-flop allows display of GO or NO GO lights at end-of-tape if MODE switch is at AUTO). Following EOTF instruction, if an auto mode, pressing STOP/RESET push-button will cause tape to search to major 00. (If START push-button is pressed, nothing will happen and the STOP/RESET push-button must be pressed twice.) If in major mode, the same operation will occur except a tape search to the thumbwheel will be initiated. When in the auto mode, the GO indicator will light at end-of-tape only if the tape ran through a TA of 00, MODE switch was left at AUTO, and the NO GO indicator did not light. If these conditions have not been met, the NO GO indicator will light at end-of-tape and auto mode.
107	EMJT	Causes tape to stop if MODE switch is at MAJOR.
177	INCM	Generates a pulse which increments the minor test counter displayed on test set LCU front panel. This pulse also resets the tape character counter to a one. This is the only instruction that is performed in branch mode.
111	STOP	Causes tape to stop; REGISTERS display is blank.
157	SDRG	Causes tape to stop; NO GO indicator lights and C-register is displayed in REGISTERS display.
013	Test LDAB	Causes the transfer of 32 bits of data from A- to B-register after reading the end-of-data character. A-register remains unchanged. If one or more data characters follow the second instruction character, the A-register is cleared and then loaded with whatever data comes from tape, prior to the end-of-data character. This instruction causes four MSB of the B-register to biz ')3Jdod with a hex-A (1010), following the shift. 2-41

Octal no.	Code	Function
003	СМАВ	Causes the comparison (logical-exclusive OR) of 32 bits of A- and B-register s to be loaded into the C-register after reading the end-of-data character. A- and B-registers remain unchanged. If a data character follows the second instruction character, the A-register is entirely cleared and then loaded with whatever data comes from tape, prior to the end- of-data character. If any bit fails to compare, the no-go flag is set. No-go flag was reset at start of instruction. The four MSB of A-register must be loaded from the tape with a hex-A (91010) to insure the A register is not programmed to saturate. Prior to this instruction, the four MSB of B-register will have been loaded with a hex-A (1010) by various instructions, to insure that B-register is not saturated. Four MSB of C-register should always be 0 after this instruction.
012	AANC	Causes the logical AND of 32 bits of A- and C-registers to be loaded into B- and C- registers after reading the end-of-data character. A-register remains unchained. If a data character follows the second instruction character, the A-register is entirely cleared and then loaded with whatever data comes from tape, prior to the end-of- data character. If any true bit is loaded in C-register, the no-fla5 is set. No-go flag was reset at start of instruction. This instruction causes four .ISB of the B-register to be loaded with hex-A (1010), following AND.
022	Branch UNBR	Causes test set to enter tape search mode and branch mode following The end-of-data character. Data loaded into A-register consists of major and minor numbers to which a branch is desired. If the major test number in A-register Is greater than the current major test number, tape reader runs forward. If less, tape reader runs in reverse direction. During tape search, tape runs at high speed- When a correct camper of the current major test number and the desired major test number occurs, tape search mode is terminated. Test set remains in branch mode and runs at low spread, ignoring all instructions but INCM, increment minor counter. unit a correct minor test compare occurs. Then branch mode is terminated and normal instruction execution returns. Branch mode may be terminated by pressing STOP/RESET push-button.
023	BRMJ	Causes test set to enter branch mode following end-of-data character In addition, tape search mode (reverse) is entered simultaneously if the desired minor test is less than or equals the current minor test. (See UNBR for tape search operation.) Only the desired minor test need be loaded into A-register, since the current major test number is in the major test register. If the desired minor test is greater than the current minor test, tape search is not entered, the tape continuing to run at low speed (for- ward) until the desired minor test is located, then branch mode is terminated and normal instruction execution returns.
024	BRNO	Causes test set to enter tape search mode and branch mode following , end-of-data character if the no-go flag is set. See UNBR for further operation. 'he data loaded into A-register following this instruction will he loaded as "long data" If the n0o-e flag is not set, and as "short data" if the no-go flea is set.
025	BNMIJ	Causes test set to enter branch mode 'following and-of-data character if the n0-go flag is set. See BRMJ for further operation. The data loaded into A-register followin g this instruction will be loaded as "long data" if the no-go flag is not set, and as "short data" if the no-go flag is set.
120	Computer interface GINT	Causes either one or both interrupt request flip-flops to be se', according, so ant' byte of data loaded into the A-register. The request remains until the interrupt at ' <niwledgc.< td=""></niwledgc.<>
117	RSET	signal is received from the computer. Causes the generation of a computer reset signal. If the computer clock i1, on, the reset signal will last long enough for the computer to begin a reset cycle If the computer clock is off, (i.e., single clock mode), the computer reset signal will remain computer clock is tuned on for least one clock. 2-42

Octal no.	Code	Function
115	RCPC	Causes the computer clock to be turned on for an indefinite period of time. Clock may be stoppe by either computer program or test set program control.
11	4RCNC	Causes the computer clock to be turned on for N (001 to 999) clocks conditionally. If, during the last nine counts of N, a memory cycle is begun, the clocks are stopped immediately.
113	RCNU	Causes the computer clock to be turned on for exactly N (001 to 999) clocks. If, during the la nine counts of N, a memory cycle is begun, the memory inhibit signal is activated for th duration of the remaining clocks.
116	STCL Input/ output interface	Causes computer clock to stop immediately after the second instruction character is read.
010	DEIP	Operates on the assumption that prior to the occurrence of end-of-data character, the compute program has performed DEIP instruction. With this condition met, the end-of-data character initiates the serial shift of the 28 low-order bits of the A-register to the EB, It is assumed th the 28 bits were loaded from tape previous to the end-of-data character; however, it is not requirement. A-register remains unchanged.
004	RMBA CIU	Causes the computer MB register (via NAD lines) to be read in parallel into the A-register, rigi justified, following the end-of-data character.
001	interface CIU	Requires 32 bits of data to be loaded into A-register from tape. Following the end-of-dat character, serial shift of the A-register to the control-indicator is initiated.
002	CIU2	Requires four bits of data, address information, to be loaded into A-register from tape. The fo address bits are shifted to the control-indicator following the end-of-data character. After th fourth bit is transmitted, the B-register is shifted for 28 bit-times, open ended. The control indicator either receives or sends 28 bits of information, depending upon whether the four address bit is a 0 or a 1, respectively. This instruction causes the B-register to be loaded with a hex-A (1010) in the four MSB, following the shift.
130	CIU3	Causes a latch to be set which supplies a ground signal to the control-indicator MODE switch wiper. Position of the MODE switch is now displayed in the REGISTERS display. The nin right-most digits correspond to the nine positions of the MODE switch. Active displa condition will be an eight; inactive, either a blank or zero. This instruction will normally the followed by a stop instruction.
	Platform interface	
035	GSP1	Verifies that the proper incremental platform angles are developed on tray 4 of the computer.
036	GSP2	Determines the capability of tray 4 to count incremental velocity pulses.
037	GSP3	Checks the operation of the self-test features that enable the AV registers to count torquing pulses.
026	Flags SIOC	Sets I/O complete
027	RIOC	Resets I/O complete
030	SSIO	Sets serial I/O control
031	RSIO	Resets serial I/O control

Octal no.	Code	Function
032	SSID	Sets serial input data
033	RSID	Resets serial input data
122	SINM	Sets inhibit memory control
123	RINM	Resets inhibit memory control
131	SINP	Sets inhibit proceed
132	RINP	Resets exhibit proceed
i 33	SCWM	Sets clear-write memory
1:3-1	RC	Resets clear-write memory
135	SIIC	Sets inhibit increment CP
136	RIIC	Resets inhibit increment CP
137	SINC	Sets initiate instruction cycle
140	RINC	Resets initiate instruction cycle
141	SICP	Sets increment CP
142 160 161 162 172 166 167 171 173 170 175 175 175 165 1633 164 017 174 125	RICP Read- Compare RCAA RCAA RCAQ RCCA RCCE RCCI RCCI RCCM RCEA RCEA RCEA RCEB RCFM TCFM RCMA RCMB RCCP RCPJ RCM RCM	Resets increment CP Sets a latch immediately (any instruction) Control logic waits until a data character is programmed after the instruction. The A-register is then cleared and loaded with tape data. If a data character is not programmed, A-register remains unchanged. Following the end-of-data character, the desired computer register is parallel loaded into the B-register and compared with the contents of the A-register, the result being loaded in C-register. If any bit fails to compare, the no-go flag is set. The no-go flag was reset at the beginning of Destruction. These instructions cause B-register to be loaded with a hex-A (1010) at the tune of the read. To achieve a true compare, A-register should be loaded with a hex-A (1010) in the four MSI'
		2-44

Octal no.	Code	Function
126	RCW2	
127	RCW3	
176	RCEX	
		(Refer to pace 2-414)
)20	RCDW	
124	RCM1	
)21	RCM2	
007	Load LACW	Causes data loaded in the A-register to be transferred to B-register. The B-register is then gated to analog channel control logic, permitting the testing of computer analog channels. If data characters are not programmed, the A-register data is not transferred to the B-register and B-register is not Gated to analog channel control logic.
014	LQJD	Causes three bits of data loaded in 'he A-register to be transferred to a holding register, which applies address information to the three QJDXX lines The holding register will be cleared after three phase C clocks, which may be under program control when this instruction is performed
144	LDCAX	Causes a clear and load operation to be performed on the specified computer register. Data is
145	LDCE	loaded in parallel.
146	LDCI	
147	LDCM	
143	LDCP	
151	LDMB	
152	LXMB	Causes a clear and load operation to be performed on the computer MB register, via the XMBXX lines. Data is loaded in parallel.
)34	LDSI	Causes data in A-register to be loaded into the discrete input holding register Signals from the holding register supply levels to the computer which simulate all of the system discrete.
100	Memory MFIL	Sets up control logic to fill or verify a block of memory (up to 1, 024 words). First operand loaded into the A-register is the starting CP address, which is loaded into the computer CP register following the first end-of-data character. Simultaneously, the computer CM register is loaded with count S, in preparation for a memory cycle. The following operands, loaded into the A-register from tape, are memory data. Memory fill operation will be described prior to memory verify. During memory fill, A-register data is loaded in parallel into the MB register. A clear-write memory cycle is initiated to write the data into the location specified by the CP register. The CP register is then incremented one count, another operand enters the A-register from tape and is loaded into he NIB register. and another memory cycle is initiated. Similar operations continue until a SMFL instruction is performed. During memory verify, following the loading of the A-register, a read-restore memory cycle is initiated which transfers memory data into the NIB register. The MB register is then loaded into the B-register and compared (logical-exclusive OR) to A-register data. Following the compare, a second read-restore is initiated This is to verify the first restore operation. The MB register is again loaded into the B-register and a second compare is made. If the compare fails, the no-go flag is set and the tape stops. The current value of CP register will be in the REGISTERS dis- play. If the STOP/RESET push-button is pressed, the display will show the C-register, which contains the result of the compare. If a failure does not occur, the CP register is incremented one count, another operand enters the A-register, two read-restore-and-compare cycles are performed. Similar operations continue until a SMFL instruction is performed.

Octal no.	Code	Function
110	HMFL	Same as MFIL, however, tape runs at high speed. Used for loading large blocks of data.
101	SMFL	Causes either a memory fill or memory verify mode to be terminated immediately. Tape reader continues to run, but shift to low speed.
102	SLMA	Causes first operand (memory address) loaded into the A-register to be loaded into the CP register, following the first end-of-data character. Simultaneously, the CM register is loaded' with count 8 in preparation for a memory cycle. A second operand may follow the first end-of-data character. Following the second end-of-data character, the A-register is loaded in parallel into the MB register and a clear-write memory cycle is initiated to write the data into the location specified by the CP register.
153	SLMC	Causes first operand (memory address) loaded into the A-register to be loaded into the C-register , following the first end-of data character. Simultaneously, the CM register is loaded with count 8 in preparation for a memory cycle. A second end-of data character, which must follow the first, causes the C-register to be loaded in parallel into the MB register, and a clear-write memory cycle to be initiated to write the data into the location specified by the CP register.
104 SREM	Causes opera	nd (memory address) loaded into the A-register to be loaded into CP register, following the end-of-data character. Simultaneously, the CM register is loaded with count 8 in preparation for a memory cycle. After the CP and CM registers have been initialized, a read-restore memory cycle is initiated to read memory data from the location specified by CP register into the MB register.
105 LVWC	Causes first or	berand (memory address) loaded into the A-register to be loaded into the CP register, following the first end-of-data character. simultaneously, the CM register is loaded with count 8 in preparation for a memory cycle. The second operand must be programmed an alternating 1-0 pattern. Following the second end-of-data character, the tape reader is stopped and the A-register loaded in parallel into the MB register. A de-write memory cycle is initiated to write the data into the location specified by the CP register. The CP register is then incremented one count, A-register is shifted right (end around) one bit, and another clear-write memory cycle is initiated. similar operations continue until the 10 low- order bit of the CP register are saturated, signifying that a 1,024-word block of memory has been loaded. Verification of the loaded data now begins. The CP register has been cleared. A read-restore memory cycle is Initiated to read the data from the location specified by the CP register into the MB register. The MB register is then loaded into B-register and compared (logical-exclusive OR) to data remaining in A-register. A second read-restore cycle is initiated, to check the first restore, and is then followed by a compare. If any comparison fail, the no-go flag is set and remains set. Following the two compares, the CP register is incremented one count and A-register is shifted right (end around) one bit. Similar operations continue until the 10 low-order bits of the CP register are saturated, signifying that a 1,024-word block has been verified. The tape reader is restarted, and the program checks, via a branch (BRNO or BNMJ), whether the no-go flag was set.
106	MVET	Causes tape reader to go into tape search mode for major test address 00. Within this major test and subsequent major tests, it is assumed there are MFIL instructions. However, the MVET instruction causes the MFIL instruction to operate in memory verify, rather than memory fill mode. After the MVET instruction is read a second time, an automatic tape rewind is performed.
005 TST1	Test Requires the k	bading of up to 40 bits of self-test data into a self-test register located in the LCU and SCU. Self-test bits are assigned functions which in general control data paths. Following the loading of the self-test register, a number of data paths have been closed, the net effect being that some data (registers or test point) will be present at the parallel input of the B-register. A clock strobe is produced, loading the B-register with whatever data was present, and clearing the self-test register. The B-register may now be compared with the expected result, via the CMAB instruction.

Octal no.	Code	Function
006	TST2	Requires the loading of up to 40 bits of self-test data into a self-test register located in the LCU and SCU. Self-test bits are assigned functions which in general control data paths. Following the loading of the self-test register, a number of data paths have been closed, the net effect being that some data (registers or test points) may be present at the parallel inputs of the B-register. The self-test bits, in self-test mode 2, may also control logic not directly con- cerned with loading data into the B-register. Assuming, first, that the B-register is to be loaded, the loading takes place by a non-self-test instruction being performed. In self-test mode 2, the performance of certain register instructions will cause data to appear at the inputs of the B-register, and will also initiate a load strobe to clock the B-register. The self- test register will be cleared by the strobe. The B-register may now be compared with the expected result, via the CMAB instruction. Self-test mode 2 may also control or simulate logic operations that do not require the B-register being loaded in parallel. In this case, a load strobe is not generated. Following whatever logic operation is performed, the B- register will in general be loaded serially. The B-register may now be compared with the expected result, via the CMAB instruction.
103	TST3	Causes the self-test of the self-test register. The operand following the instruction will consist of 72 bits, arranged as 18 data characters. The data will be loaded byte se rially into the self-test register and the A-register simultaneously. After eight bytes (data characters), the A-register is loaded. Shifting continues, however, with the least significant data being lost. At the completion of the 10th byte, the self-test register is loaded. Beginning with the 11th byte, the output of the A-register and self-test register are compared (logical-exclusive OR) bit serially. If any bit fails to compare, the TEST SET FAULT indicator lights, the tape reader sops, and the REGISTERS display shows the internal error register. The display can be interpreted by referring to TM 11-6625-2441-12, and should indicate that the error is in the self-test register.
121	EVPC	Sets up control logic to test the state of the vertical party register, following the end-of-data character. Each of the seven active tape channels (1, 2, 3, 4, 5, 6, 8) cause its respective flip-flop, in the vertical parity register, to toggle each time the channel is in the t rue state. The tape assembler program keeps track of the parity of each channel. When an EVPC instruction is programmed, the assembler decides what additional tape character, either data or end-of-data, is required to cause the vertical parity register to reach the 0000000 state following the end-of-data character. The register is checked, and if not all O's, the TEST SET FAULT indicator lights, the tape stops, and the REGISTERS display shows the internal error register. The display should indicate that a vertical parity error exists.

(5) Data word A data word, consisting of 1 to 28 bits, is applied directly to the A-register to be processed per the preceding instruction. At the end of the data word, an end-of-data pulse is generated and the instruction is processed.

(6) Minor test counter. This counter provides the number of the minor test for display. The counter is incremented one count by an increment minor test counter instruction, and resets at the beginning of a major test.

#### 2-21. Program Listing

The program listing, appendix B, is a graphic presentation of the self-test program tape. Correlation between the test set TEST NUMBER MAJOR MINOR indicator and the listing will provide information such as test description, test

#### **CHAPTER 3**

#### **GENERAL SUPPORT MAINTENANCE**

#### Section I. GENERAL

#### 3-1. Scope

General support maintenance includes troubleshooting and removal and replacement procedure for the test set. Troubleshooting procedure include charts for troubleshooting and resistance measurements. Removal and replacement procedures are for discrete components an' assemblies of the test set. In the removal an( replacement procedures, when full reference designations are used in paragraph headings, references to the same item within that paragraph will be abbreviated.

#### 3-2. Test Equipment, Tools, and Materials Required

*a. Test Equipment.* The following chart lists all test equipment essential for troubleshooting the test set.

ltem	Manufacturer and part no.	Use
Voltmeter (DVM) Oscilloscope AN/USM-281A (with Plug-In Units PL1186/USM-281A and PL-1187/USM-281A).	Non Linear Systems Model X-2	Verifying predetermined voltage measurements. Displaying test signal waveforms; measuring frequency and voltage.
Tape Reader AN/USA-34.		Transferring information from the diagnostic and test tapes to the test set.
Multimeter AN/USM-223.		Checking voltages, continuity. and resistance during trouble- shooting.

b. *Tools.* The following tools are essential for maintenance of the test set.

Manufacturer and	
part no.	Use
	Providing tools for general use.
Daniels MH750	Attaching wire to replacement pins for Bendix and Hughes type connectors.
AMP 69535	Attaching wires to AIP type connector pins using clips.
	<i>part no.</i> Daniels MH750

		Manufacturer and	
	Itern	part no.	Use
	Mandrel.	AMP 69545-1	Used with Term-Point service tool to accommodate 2n-gage wire_ and AMP 67042-2 clips.
	Extractor-locator tool.	AMP 69357-5.	Removing clips from damaged AMP type connector pins, re- locating clips and wares still attached to connector pins.
	Pull test tool.	AMP 69358-6.	Inspecting Term-Point Terminations.
	Removal tools.	Bendix 11-8675-16, 11 -867 5 -20, 11-8675-22, 11 -8675-24	Removing damaged pins from Bendix type connectors.
	Insertion tools	Bendix 11-8674-16, ) 11 -8674 -20, 11-8674 -222, 11 -8674 -24	Inserting replacement pins in Bendix type connectors.
	Contact locator heads.	Bendix 11-8673-4, . 11-8673-6, > 11-8673-7)	Used in conjunction with Bendix removal and insertion tools (installed in crimping tool M3H750).
	Torque wrench.	Torque Controls, Inc. Kit 2.	Torquing of hardware.
	Insertion tool,	Hughes TW0221TOOO.	Inserting replacement pins in Hughes type connectors.
т.	Removal tool.	Hughes Hughes type connectors.	Removing damaged pins from
	wire stripper.	GGG-S-793A.	Stripping insulation from wires.
	Wire stripper. Model 100.	K. Miller	Trimming wire, for use wit]h ' termi- Point service tool.
	Heat gun.	Master Appliance HG-751J.	Shrinking heat-shrinkable sleevin4.

# c. materials. The following materials are essential for maintenance of the test set.

ltem	FSN	Use
Cleaning compound.	7930-395-9542.	Cleaning solder connections.
Lint-free cloth.	8305-170-5062.	Cleaning equipment.
Camel's hair brush (commercial).		Cleaning solder connections.
Acetone (0-A-51D).		Cleaning mechanical parts.
Insulation sleeving, electrical, heat- shrinkable (MIL-I-23053	·).	Providing electrical isolation between connector pins; supporting small-gage wires.

Item	FSN	Use
Sealant, grade C (Loctite, MIL-S-22473).		Locking (liquid used in lieu of mechanical locking device).
Perchloroethylene (commercial).		Cleaning electrical parts.
Freon (PCA).		Removing residue left by other cleaning compounds

#### SECTION II. TROUBLESHOOTING

#### 3-3. Troubleshooting Procedures

Troubleshooting the test set at general support maintenance is a continuation of the organizational maintenance troubleshooting procedures contained in TM 11-6625-2441-12. Since all plugging modules, indicator lamps, and switch knobs are replaced at organizational maintenance, the general support maintenance troubleshooting chart isolates malfunctions to discrete components and cables. The sequence numbers in the troubleshooting chart are keyed to the sequence numbers in the daily preventive maintenance checks and services chart in TM 11-6625-2441-12. The Corrective action column lists discrete components

which could cause the trouble indication. In all tests, the possibility of intermittent troubles should not be overlooked. If this type of trouble is present, it may be made to appear by tapping or jarring the equipment. Make a close inspection of the wiring and connections in the units of the test set. Continuity and resistance measurements, referenced to the wire and circuit lists in appendix C, volume 2 and various figures in chapter 5, should be used to locate faulty wiring and connections. Upon completion of repairs, perform the self-test procedures in TM 11-6625-2441-12. The self test program listing may be used as an aid in following the operation of the self-test tape.

#### 3-4. Troubleshooting Chart

Step no.	Trouble symptom	Procedure trouble	Corrective action
3	Switch does not work smoothly	Faulty switch	Replace switch (para 3-7, 3-8, 3-18, 3-29, 3-32, 3-33, or 3-35)
4	Trouble symptoms are as follows:		
	a. SCU blowers not operating.	<ul> <li>a. Probable troubles are as follows:</li> <li>(1) Faulty blower 2AIBI, B2, or B3.</li> <li>(2) Faulty capacitor 2A1 C1, C3, or C4.</li> <li>(3) Faulty hybrid 2A1HY2</li> <li>(4) Faulty circuit breaker 2A1CB4.</li> </ul>	<ul> <li>a. Corrective actions are as follows:</li> <li>(1) Replace blower 2AlBl, B2, or B3 (para 3-14 and 3-15).</li> <li>(2) Replace capacitor 2AlCl, C3, or C4 (para 3-16)</li> <li>(3) Higher level of maintenance.</li> <li>(4) Replace circuit breaker 2A1CB4 (para 3-13).</li> </ul>
	b. LCU blowers not operating.	<ul> <li>b. Probable troubles are as follows:</li> <li>(1) Faulty blower 1A1B1 or B2.or</li> </ul>	<ul> <li>b. Corrective actions are as follows:</li> <li>(1) Replace blower IAIBI B2 (para 3-38).</li> </ul>

step no.	Trouble symptom	Procedure trouble	Corrective action
		(2) Faulty capacitor 1A1 C1 or C2.	(2) Replace capacitor IAIC1 or C2 (para 3-39).
		(3) Faulty hybrid 2A1HY1	.(3) Higher level of mainte- nance.
		(4) Faulty circuit breaker 2A1CB4.	(4) Replace circuit breaker 2A1CB4 (para 3-13).
	c. POWER PRIMARY indicator does not light	c. Faulty indicator assembly .2AIDS5 or capacitor	c. Replace indicator assembly 2A1C2.2AIDS5 (para 3-6) o capacitor 2A1C2 (para 3-16
	d. POWER AC indicator dose	d. Probable troubles are as	d. Corrective actions are as
	not light	.follows: (1) Faulty indicator assembly 2AIDS4.bly	follows: (1) Replace indicator assem- 2AIDS4 (para 3-6).
		(2) Faulty POWER AC switch 2A1S3	(2) Replace switch 2A1S3 .(para 3-18).
5	Trouble symptoms are as follows:		
	<ul> <li>POWER TEST SET indicator a. Pro does not light.</li> </ul>	bable troubles are as follows:	<ul> <li>Corrective actions are as follows:</li> </ul>
	does not light.	(1) Faulty indicator assembly 1A1A5DS11.bly	(1) Replace indicator assem- 1A1A5DS11.
		(2) Faulty TEST SET switch 1A1A5S7.	(2) Replace switch IAIA5S7 (para 3-32).
	b. TEST NUMBER indicator b. Pro		b. Corrective actions are as
	does not display MAJOR 00 MINOR 00 and REGISTERS display is not blank	follows: (1) Faulty TEST NUMBER .indicator assembly(s) 1A1A5DS8A through 1A1A5DS8D.	follows: (1) Replace indicator assem- bly(s) IAIA5DSSA through 1A1A5DS8D (para 3-30).
		(2) Faulty REGISTERS dis- play indicator assembly(s) 1A1A5DS7A through 1AIA5DS7L.	(2) Replace indicator assem- bly(s) 1AIA5DS7A through I1AA5DS7L (para 3-30).
	c. Tape drives off reel in for- ward direction.	c. Faulty START switch 1A1A5S2	c. Replace switch IAIA5S2 (para 3-29).
	d. Tape drives off reel in reverse direction.	d. Faulty component board 2A1A4.2A1A4	d. Replace component board (para 3-17).
	e. Tape drives in forward or reverse direction and stops.	e. Faulty component board 2A1A4.2A1A4	e. Replace component board (para 3-17).
6	Any or all SCU indicators do not	Probable troubles are as follows:	Corrective actions are as follow
	light.	(1) Faulty LAMP TEST switch 2A1S2.	(1) Replace switch 2A1S2 (para 3-8).
		(2) Faulty SCU indicator as sembly(s).assembly(s)	-(2) Replace SCU indicator (para 3-6).
		(3) Faulty component board 2A1A4.2A1A4	(3) Replace component board (para 3-17).

Step no.	Trouble symptom	Procedure trouble	Corrective action
7	Trouble symptoms are as follows:		
	<ul> <li>Any or all LCU indicators do not light.</li> </ul>	<ul> <li>a. Probable troubles are as follows:</li> <li>(1) Faulty LAMP TEST switch 1A1A5S8.</li> <li>(2) Faulty LCU indicator assembly(s).assembly(s)</li> </ul>	<ul> <li>a. Corrective actions are as follows: <ul> <li>(1) Replace switch IAIA5S8</li> <li>(para 3-29).</li> </ul> </li> <li>(2) Replace LCU indicator (para 3-28).</li> </ul>
	<ul> <li>REGISTERS display does not indicate all 8's.</li> </ul>	<ul> <li>b. Faulty REGISTERS display indicator assembly(s) 1A1A5DS7A through 1A1A5DS7L.</li> </ul>	b. Replace indicator assembly(s 1A1A5DS7A through 1A1A5DS7L (para 3-30).
	c. REGISTERS display is c. Fau blank and TEST NUMBER indicator displays MAJOR 00 MINOR 00.	lty component board 2A1A4.2A1A4	c. Replace component board (para 3-17).
8	Any or all voltages not present	Faulty VOLTAGE MONITOR or not as specified.	Replace switch 2A1SI (para switch 2A1S1.3-37).
9	Trouble symptoms are as follows:		
	a NCU POWER 115 VAC, 400 Hz indicator does not	a. Faulty NCU POWER 115 VAC, 400 Hz circuit breaker light.	a. Replace circuit breaker 2AICB1 (para 3-13). 2AICB1.
	<ul> <li>b. Oscilloscope indication not as specified or not present (73.6 (±7.4)V p-p).</li> </ul>	<ul> <li>b. Probable troubles are as follows:</li> <li>(1) Faulty SCU NCU POWER 115 VAC, 400 Hz circuit2AlCB1 breaker 2A1CB1.</li> <li>(2) Faulty VOLTAGE MONI- TOR switch 2A1S1.</li> <li>(3) Faulty transformer 2AITI. 2A1T1</li> </ul>	<ul> <li>b. Corrective actions are as follows: <ul> <li>(1) Replace circuit breaker</li> <li>(para 3-13).</li> </ul> </li> <li>(2) Replace switch 2A1S1 <ul> <li>(para 3-7).</li> </ul> </li> <li>(3) Replace transformer <ul> <li>(para 3-20).</li> </ul> </li> </ul>
	c. NCU POWER 28 VDC indi- cator does not light.	c. Faulty NCU POWER 28 VDC circuit breaker 2A1CB2.2A1CB2	c. Replace circuit breaker (para 3-13).
	d. DVM indication not and. specified .switch	d. Faulty VOLTAGE MONITOR 2AIS1	d. Replace switch 2A1Sl .(para 3-7).
10	Trouble symptoms are as follows:		
	a. CIU POWER 28 VDC indi- cator does not light.	a. Probable troubles are as follows:	a. Corrective actions are as follows:
		<ul> <li>(1) Faulty component board 2A1A4.2A1A4</li> <li>(2) Faulty CIU POWER 28 VDC circuit breaker2A1CB3 2A1CB3.</li> </ul>	<ol> <li>(1) Replace component board (para 3-17).</li> <li>(2) Replace circuit breaker (para 3-13).</li> </ol>
	<ul> <li>DVM indication not as specified.</li> </ul>	b. Faulty VOLTAGE MONI- TOR switch 2AISI.	b. Replace switch 2AIS1 (para 3-7).
		3-5	

Step no.	Trouble symptom		Procedure trouble	Corrective action
11	Trouble symptoms are as follows:			
	a. Tape does not drive	follows (1) If replace 1A1A3/ correct trouble	troubles are as ement of card A (25, 29) did not trouble, probable is faulty oscillator	<ul> <li>a. Corrective actions are as follows:</li> <li>(1) Replace oscillator 1A1Y1 (para 3-40),</li> </ul>
		1A1A1/ not corr probab STOP/I	ement of card A (8, 16, 17) did rect trouble, e trouble is faulty RESET push-	(2) Replace switch iAlA5S3 (para 3-29).
		(3) If replace 1A1A2/ not com probab SCU ca (4) If replace 1A1A1/ 20, 22) trouble is STAI	switch 1 A1 A5S3. ment of card A (23, 24, 25) did rect trouble, le trouble is LCU/ ables. ment. of card A (6, 16, 18, 19, did not correct probable trouble RT push-button 2A1A5S2.	<ul> <li>(3) Check continuity (para 3-5, fig. 5-8 or 5-9) and replace faulty cable or connector (para 3-41 through 3-47)).</li> <li>(4) Replace switch 2A1A5S2 (para 3-29).</li> </ul>
	<ul> <li>TEST NUMBER minor indi- cator steps correctly but REGISTERS display is not as specified.</li> </ul>	b. Faulty SC	CUILCU cables.	<ul> <li>b. Check continuity (para 3-5, fig. 5-8 or 5 -9) and replace faulty cable or connector (para 3-41 through 3-47).</li> </ul>
	c. TEST NUMBER indicator and REGISTERS display step cor- rectly but when tape stops, in- dications are not as specified.		ST NUIBER indi- ssembly IAIA5DS8C	c. Replace indicator assembly 1A1A5DS8C or D (para 3-30).
14	TEST NUMBER indication not as specified.	•	NUMBER indicator bly IAIA5DS8C or D.	Replace indicator assembly IAIA5DSSC or D (para 3-30).
16	Tape does not drive.	Faulty STOF	P/RESET switch	Replace switch 1A1A5S3 (para
C	Adapter, Self Test MS-8586/ ASI Continuity and Resistance Meas		Resistor	Value (ohms)
(	fig. 3-1 and 5-8)		R1	200
			A1R2	300
	figure 3-1 for location and referen		A1 R3	100
	ons of the self-test adapter resist		A1R4 A1R5	1,000
	Use the test equipment specified easurement of resistive loads The		A1R5 A1R6	47, 000 4, 000
	s the resistors and values.		A1R7	4,000
			A1R8	2,000

Resistor	value (ohms)	AIR12	2,000
		AIR13	680
AiR8	2,000	AIR14	300
AIR9	2,000	AIR15	2,490
AiR10	2,000	AIR16	2,490
AIR11	2,000	AIR17	100

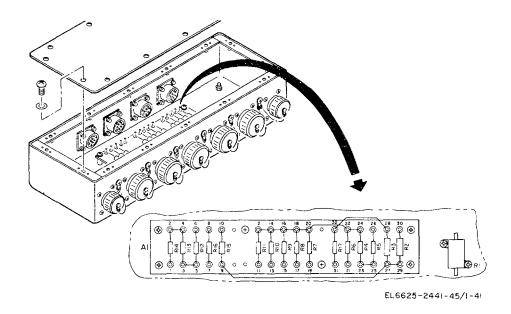


Figure 3-1. Adapter, Self Test MXI-8586/ASMf-386, resistor location diagram.

#### Section III. REMOVAL AND REPLACEMENT

#### 3-6. Removal and Replacement of Indicators 2AIDSI through 2AIDS9 (fig. 3-2)

The following removal and replacement procedures apply to DS1 through DS5 (front panel) and DS6 through DS9 (test panel).

a. Removal

(1) Loosen 12 stud nuts (1) that secure chassis assembly (2) to combination case.

#### NOTE

Card cages 2AIAI and 2A1A2 are connected mechanically. Captive screws on both card cages must be loosened and card cages opened together (2) Loosen required number of captive screws (3) that secure card cage(s) (4) to chassis assembly (2) and swing card cage(s) open.

(3) Tag and unsolder wires from terminals of faulty indicator.

(4) Remove nut (5) and lockwasher (6); remove indicator (7) and 0-ring (8) from front panel (9) or test panel (62).

b. Replacement

(1) Attach 0-ring (8) and indicator (7) to front panel (9) or test panel (62) with lockwasher (6) and nut (5).

(2) Solder tagged wires to proper terminals of replacement indicator.

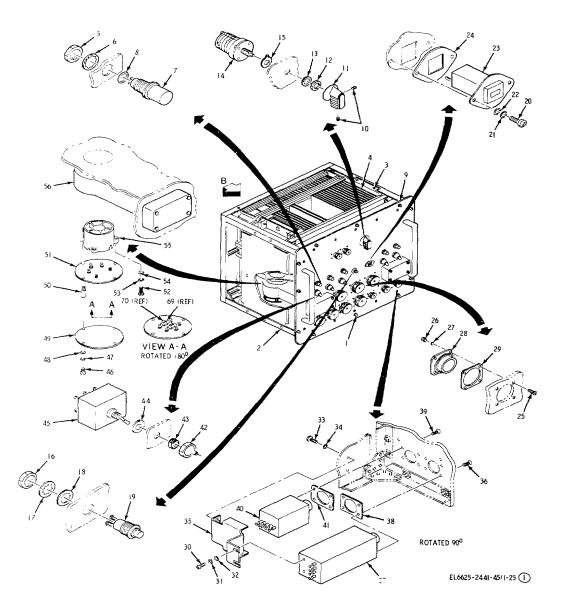


Figure 3-20 (1). Signal Conditioning Unit TS-2913/ASM-386, exploded view (part 1 of 3)

- Stud nut (12) 1
- 2 3 Chassis assembly
- Captive screw (6)
- 4 Card cage (3)
- 5 Nut (9) 6
- Lockwasher (9) 7
- Indicator (9, 2AIDS1 through 2 AIDS9
- 8 0-ring (9)
- Front panel 9
- 10 Setscrew (2)
- Knob 11
- 12 Nut
- Lockwasher 13
- 14 Switch 2A1S1
- Keywasher 15
- 16 Nut
- Lockwasher 17
- 18 Flatwasher
- Switch 2A1S2 19

- 20 Screw (4)
- Lockwasher (4) 21
- 22 flatwasher (4)
- 23 Elapsed-time meter (2; 2A1M1, IAIA5MI)
- 24 Emi gasket (2)
- 25 Screw (40)
- Nut (40) 26
- Nut (40) 27
- Connectors (10, 2A1J3 through 28 2A1J2)
- 29 Emi gasket (10)
- 30 Nt (2
- Lockwasher (2) 31
- 32 Flatwasher (2)
- Screw (2) 33
- 34 Flatwasher (2)
- 35 Filter support bracket
- 36 Screw (4)
- 37 Filter 2A1J2

Emi gasket Screw (4) 38 39 40 Filter 2À1J1 41 Emi gasket 42 Boot (4) Boot adapter (4) 43 44 Keywasher (4) 45 Circuit breaker (4, 2AICB1 through 2A1CB4) Screw (4 46 47 Lockwasher 48 flatwasher (4) 49 Protection plate 50 Spacer (4) 51 Air inlet duct cover Screw (3) 52 53 Lockwasher (3) flatwasher (3) 54 55 Blower 2A1Br 56 Air inlet duct

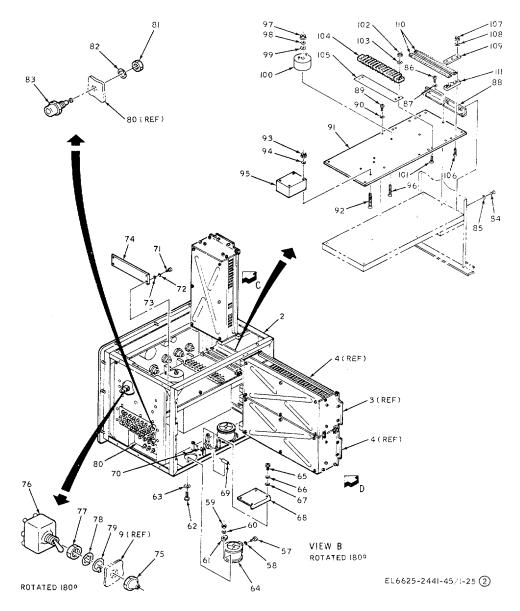
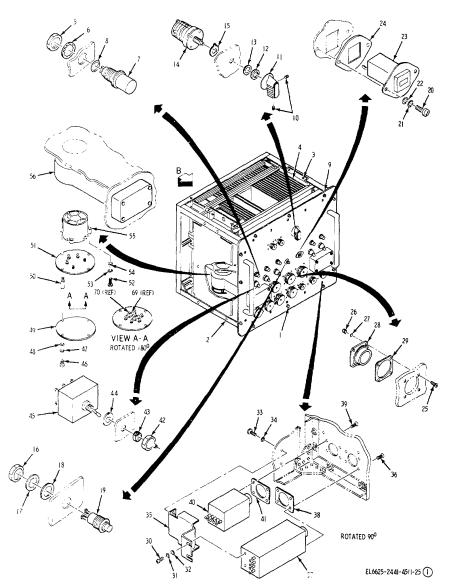


Figure 3-2 (2). Signal Conditioning Unit TS-2913/ASM-386, exploded view (part 2 of 3)

57	Screw (6)	75	Boot (4)	93	Locknut (4)
58	Flatwasher (6)	76	Switch (4, 2A1S3 through	94	Flatwasher (4)
59	Nut (6)		2A1S6)	95	Transformer 2AITI
60	Flatwasher (6)	77	Nut (4)	96	Screw
61	Cleat (6)	78	Lockwasher (4)	97	Locknut
62	Screw (6)	79	Keywasher (4)	98	Lockwasher
63	Flatwasher (6)	80	Test panel	99	Flatwasher
64	Blower (2, 2A1B2 and	81	Nut (51)	100	Reactor 2AILI
2A	1B3)	82	Lockwasher (51)	101	Screw (4)
65	Screw (4)	83	Test point connector (51, 2AIJ13 through	102	Locknut (4)
66	Lockwasher (4)		2A1J63)	103	Flatwasher (4)
67	Flatwasher (4)	84	Screw (6)	104	Terminal board 2A1TB1
68	Cover	85	Flatwasher (6)	105	Marker strip
69	Capacitor (4, 2AICI through	86	Screw (6)	106	Screw (6)
2A	1C4)	87	Flatwasher (6)	107	Locknut (6)
70	Clip (4)	88	Angle bracket (2)	108	Flatwasher (6)
71	Screw (4)	89	Screw (4)	109	Bus bar retainer (2)
72	Lockwasher (4)	90	Flatwasher (4)	110	Bus bar (2, 2A1W2, and
73	Flatwasher (4)	91	Plate		2A1W3)
74	Component board 2A1A4	92	Screw (4)	111 B	us bar bracket (2)



Signal (3) Signal Conditioning- Unit TS-2913/ASM-386, exploded view (part 3 of 3)

112	Connector retaining screw (14)	130	Spacer (14)
113	Connector (14, 2AtP1 through 2A1P6, and AIPI	131	Spacer (28)
	through I AIP8)	132	Pin (2)
114	Screw (28)	133	Hinge, pin t2)
	ll5 Nut i28)	134	Nylon shim washers (4 maximum)
116	Lockwasher ' 28 I	135	Card cage 2A1S 3
117	Flatwasher (2'8)	136	Screw (12)
118	Card cage connectors (11)	137	Lockwasher (12)
119	Screw (42)	138	Flatwasher (12)
120	Flatwasher (-12)	139	Bushing (12)
121	Spacer (42)	140	Ground strap (6)
122	Cover (7)	141	Screw (18)
123	Standoff (11)	142	Flatwasher (IS)
124	Screw (91)	14:3	Connecting plate (9)
125	Lockwasher (91)	144	Pin (12)
126	Flatwasher (91)	145	Hinge pin (6)
127	Bushing (91)	146	Nvlon shim washers (24 maximum)
128	Connector plate assembly (7)	147	Card cage (6, 2A] AI, 2AIA2 IAIAI through
129	Spacer (7) 1A2A4)		

(3) Secure card cage(s) (4) to chassis assembly (2) with captive screws (3).

(4) Slide chassis assembly (2) into combination case and tighten 12 stud nuts.

# 3-7. Removal and Replacement

of Switch 2AISI

(fig. 3-2)

a. Removal

(1) Refer to paragraph 3-6a(1) and (2) to remove chassis assembly from combination case and swing card cage open.

(2) Tag and unsolder wires from terminals of switch S1.

(3) Loosen two setscrews (10) that secure knob (11) to switch S1.

(4) Remove nut (12) and lockwasher (13); remove switch S1 (14) and keywasher (15) from front panel (9).

b. Replacement

(1) Attach keywasher (15) and switch S1 (14) to front panel (9) with lockwasher (13) and nut (12).

(2) Solder tagged wires to proper terminals of switch S1.

(3) Secure knob (11) to switch S1 with two setscrews (10).

(4) Refer to paragraph 3-6b(3) and (4) to secure card cage to chassis assembly and install chassis assembly in combination case.

# 3-8. Removal and Replacement of Switch 2AIS2

(fig. 3-2)

a. Removal

(1) Refer to paragraph 3-6a(1) and (2) to remove chassis assembly from combination case and swing card cage open.

(2) Tag and unsolder wires from terminals of switch S2.

(3) Remove nut (16), lockwasher (17), and flatwasher (18); remove switch S2 (19) from front panel (9).

# b. Replacement

(1) Attach switch S2 (19) to front panel (9) with flatwasher (18), lockwasher (17), and nut (16).

(2) Solder tagged wires to proper terminals of switch S2.

(3) Refer to paragraph 3-6b(3) and (4) to secure card cage to chassis assembly and install chassis assembly in combination case.

#### 3-9. Removal and Replacement of Elapsed-Time Meters 2AIM1 and 1AIA5MI

a. Removal

(1) Remove two screws (20), lockwashers (21), and flatwashers (22); carefully remove elapsed-time meter (23) and emi gasket (24) from front panel.

(2) Tag and unsolder wires from elapsed- time meter terminals.

b. Replacement

(1) Solder tagged wires to proper elapsed- time meter terminals.

(2) Attach emi gasket (24) and elapsed-time meter (23) to front panel using two flatwashers (22), lockwashers (21), and screws (2).

3-10 . Removal and Replacement of Front Panel Connectors 2A1J3 through 2AlJ12 (fig. 3-2)

a. Removal

(1) Refer to paragraph 3-6a(1) and (2) to remove chassis assembly from combination case and swing card cages open.

(2) Tag and remove wires from faulty connector.

(3) Remove four screws (25), nuts (26), and flatwashers (27); remove connector (28) and emi gasket (29) from front panel.

#### b. Replacement

(1) Attach emi gasket (29) and connector (28) to front panel using four flatwashers (27), nuts (26). and screws (25).

(2) Install tagged wires in connector.

(3) Refer to paragraph 3-6b(3) and (4) to secure card cages to chassis assembly and install chassis assembly in combination case.

#### 3-11. Removal and Replacement of Filter 2A1J2 (fig. 3-2)

a. Removal

(1) Refer to paragraph 3-6a(1) and (2) to remove chassis assembly from combination case and swing card cages open.

(2) Remove two nuts (30), lockwashers (32), flatwashers (32), screws (33), and flatwashers (34); remove filter support bracket (35).

(3) Tag and unsolder wires from filter J2 terminals.

(4) Remove four screws (36); remove filter J2 (37) and emi gasket (38) from front panel.

#### b. Replacement

(1) Attach emi gasket (38) and filter J2 (37) to front panel using four screws (36).

(2) Solder tagged wires to filter J2 terminals.

(3) Mount filter support bracket (35) using two flatwashers (34), screws (33, flatwashers (32), lockwashers (31), and nuts (30).

(4) Refer to paragraph 3-6b(3) and (4) to secure card cages to chassis assembly and install chassis assembly in combination case.

3-12. Removal and Replacement of Filter 2A1J1 (fig. 3-2)

### a. Removal

(1) Refer to paragraph 3-6a(1) and (2) to remove chassis assembly from combination case and swing card cages open.

(2) Remove two nuts (30), lockwashers (32), flatwashers (32), screws (33). and flatwashers (34); remove filter support bracket (35).

(3) Tag and unsolder wires from filter J1 terminals.

(4) Remove four screws (39); remove filter J1 (40) and emi gasket (41) from front panel.

## b. Replacement

(1) Attach emi gasket (41) and filter J1 (40) to front panel using four screws (39).

(2) Solder tagged wires to filter J1 terminals.

(3) Mount filter support bracket (35) using two flatwashers (34), screws (33), flatwashers (32). lockwashers (31), and nuts (30).

(4) Refer to paragraph 3-6b(3) and (4) to secure card cages to chassis assembly and install chassis assembly in combination case.

#### 3-13. Removal and Replacement of Circuit Breakers 2A1CB1 through 2A1CB4 (fig. 3-2)

a. Removal

(1) Refer to paragraph 3--6a(1) and (2) to remove chassis assembly from combination case and swing card cages open.

(2) Tag and unsolder wires from terminals of faulty circuit breaker.

(3) Remove boot (42) and boot adapter (43); remove keywasher (44) and circuit breaker (45) from front panel (9).

#### b. Replacement

(1) Attach keywasher (44) and circuit breaker (45) to front panel (9) with boot adapter (43) and boot (42).

(2) Solder tagged wires to proper terminals of replacement circuit breaker.

(3) Refer to paragraph 3-6b(3) and (4) to secure card cages to chassis assembly and install chassis assembly in combination case.

#### 3-14 . Removal and Replacement of Blower 2A1B1 (fig. 3-2)

#### a. Removal

(1) Refer to paragraph 3-6a(1) to remove chassis assembly from combination case; carefully place chassis assembly upside down on work- bench.

(2) Remove four screws (46), lockwashers (47), and flatwashers (48); remove protection plate (49).

(3) Remove four spacers (50); remove air inlet duct cover (51).

(4) Tag and unsolder wires from terminals of blower Bl.

(5) Remove three screws (52), lockwashers (53), and flatwashers (54); remove blower Bl (55) from air inlet duct (56).

#### b. Replacement

(1) Attach blower BI (55) to air inlet duct (56) with three flatwashers (54), lockwashers (53), and screws (52).

(2) Solder tagged wires to proper terminals of blower Bl.

(3) Secure air inlet duct cover (51) to air inlet duct (56) with four spacers (50).

(4) Attach protection plate (49) to spacers (50) with four flatwashers (48), lockwashers (47), and screws (46).

(5) Refer to paragraph 3-6b(4) to install chassis assembly in combination case.

3-15 . Removal and Replacement of Blower 2A1B2 and 2A1B3 (fig. 3-2)

a. Removal

(1) Refer to paragraph 3-6a(1) and (2) to remove chassis assembly from combination case and swing card cages open.

(2) Tag wires attached to terminals of faulty blower; remove three screws (57) and flatwashers (58) and remove wires from faulty blower.

(3) Remove three nuts (59), flatwashers (60), cleats (61), screws (62), and flatwashers (63); remove blower (64).

b. Replacement

(1) Attach blower (64) to chassis assembly (2) with three flatwashers (63), screws (62), cleats (61), flatwashers (60), and nuts (59).

(2) Attach tagged wires to proper terminals of replacement blower with three flatwashers (58) and screws (57).

(3) Refer to paragraph 3-6b(3) and (4) to secure card cages to chassis assembly and install chassis assembly in combination case.

#### 3-16. Removal and Replacement of Capacitors 2AIC1 through 2A1C4 (fig. 3-2)

#### a. Removal

(1) Refer to paragraph 3-6a(1) to remove chassis assembly from combination case.

(2) Proceed as follows to remove capacitors C3 and C4:

(a) Refer to paragraph 3-6a(2) to swing card cages open from chassis assembly.

(b) Remove four screws (65), lockwashers (66), and flatwashers (67); remove capacitor cover (68).

( c) Unsolder leads of faulty capacitor (69) and remove from clip (70).

(3) Proceed as follows to remove capacitors CI and C2:

(a) Carefully place chassis assembly (2) upside down on workbench.

(b) Perform procedure in paragraph 3-14a(2).

(c) Unsolder leads of faulty capacitor (69) and remove from clip (70).

b. Replacement

(1) Proceed as follows to replace capacitors C1 and C2:

(a) Place capacitor (69) in clip (70) and solder leads to terminals.

(b) Perform procedure in paragraph 3-14b(4).

(c) Place chassis assembly (2) right side up on workbench.

(2) Proceed as follows to replace capacitors C3 and C4:

(a) Place capacitor (69) in clip (70) and solder leads to terminals.

(b) Attach capacitor cover (68) to chassis assembly (2) with four flatwashers (67), lock- washers (66), and screws (65).

(c) Refer to paragraph 3-6b(3) to secure card cages to chassis assembly.

(3) Refer to paragraph 3-6b(4) to install chassis assembly in combination case.

#### 3-17. Removal and Replacement of Component Board 2A1A4 (fig. 3-2)

a. Removal

(1) Refer to paragraph 3-6a(1) and (2) above to remove chassis assembly from combination case and swing card cages open.

(2) Tag and unsolder wires attached to component board A4.

(3) Remove four screws (71), lockwashers (72), and flatwashers (73); remove component board A4 (74).

b. Replacement

(1) Attach component board A4 (74) to chassis assembly (2) with four flatwashers (73), lockwashers (72), and screws (71).

(2) Solder tagged wires to proper terminals of component board A4.

(3) Refer to paragraph 3-6b(3) and (4) to secure card cages to assembly and install chassis assembly in combination case.

#### 3-18. Removal and Replacement of Switches 2A1S3 through 2A1S6 (fig. 3-2)

The following removal and replacement procedures apply to toggle switches S3 (front panel) and S4 through S6 (test panel).

a. Removal

(1) Refer to paragraph 3-6a(1) and (2) to remove chassis assembly from combination case and swing card cages open.

(2) Tag and unsolder wires attached to terminals of faulty switch.

(3) Remove boot (75); remove switch (76), nut (77), lockwasher (78), and keywasher (79) from test panel (SO) or front panel (9).

b. Replacement

(1) Attach keywasher (79), lockwasher (78), nut (77) and switch (76) to test panel (80) or front panel (9) with boot (75); tighten nut (77).

(2) Solder tagged wires to proper terminals of replacement switch,

(3) Refer to paragraph 3-66(3) and (4) to secure card cages to chassis assembly and install chassis assembly in combination case.

#### 3-19 . Removal and Replacement of Test Point Connectors 2A1J13 through 2A1J63 (fig. 3-2)

a. Removal

(1) Refer to paragraph 3-6a(1) and (2) to remove chassis assembly from combination case and swing card cage open.

(2) Unsolder wire(s) from test point connector terminal.

(3) Remove nut (81) and lockwasher (82); remove test point connector (83) from TEST POINT panel.

b. Replacement

(1) Attach test point connector (83) to TEST POINT panel using lockwasher (82) and nut (81).

(2) Solder wire(s) to test point connector terminal.

(3) Refer to paragraph 3-6b(3) and (4) to secure card cage to chassis assembly and install chassis assembly in combination case.

#### **3-20.** Removal and Replacement of Transformer 2A1T1 (fig. 3-2)

#### a. Removal

(1) Refer to paragraph 3-6a(1) and (2) to remove chassis assembly from combination case and swing card cages open.

(2) Tag and unsolder wires from transformer T1 terminals.

(3) Remove six screws (84), flatwashers (85), screws (86), and flatwashers (87); remove two angle brackets (88).

(4) Remove four screws (89) and flat- washers (90); carefully lift plate (91) from heat exchanger.

(5) Remove four screws (92), locknuts (93), and flatwashers (94); remove transformer T1 (95) from plate (91).

b. Replacement

(1) Attach transformer T1 (95) to plate (91) using four flatwashers (94), locknuts (93), and screws (92).

(2) Attach plate (91) to heat exchanger using four flatwashers (90) and screws (89).

(3) Install two angle brackets (88) using six flatwashers (87), screws (86), flatwashers (85), and screws (84).

(4) Solder tagged wires to transformer T1 terminals.

(5) Refer to paragraphs 3-6b(3) and (4) to secure card cages to chassis assembly and install chassis assembly in combination case.

#### 3-21 . Removal and Replacement of Reactor 2AIL1 (fig. 3-2)

a. Removal

(1) Refer to paragraph 3-6a(1) and (2) to remove chassis assembly from combination case and swing card cages open.

(2) Tag and unsolder wires from reactor L1 terminals.

(3) Remove six screws (84), flatwashers (85), screws (86), and flatwashers (87): remove two angle brackets (88).

(4) Remove four screws (89) and flat- washers (90); carefully lift plate (91) from heat exchanger.

(5) Remove screw (96), locknut (97), lock- washer (98), and flatwasher (99); remove reactor L1 (100) from plate (91).

b. Replacement

(1) Attach reactor LI (100) to plate (91) using flatwasher (99), lockwasher (98), locknut (97), and screw (96).

(2) Attach plate (91) to heat exchanger using four flatwashers (90) and screws (89).

(3) Install two angle brackets (88) using six flatwashers (87) screws (86), flatwashers (85), and screws (84)

(4) Solder -tagged wires to reactor L1 terminals.

(5) Refer to paragraph 3-6b(3) and (4) to secure card cages to chassis assembly and install chassis assembly : combination case.

#### 3-22 . Removal and Replacement of Terminal Board 2A]TBI (fig. 3-2)

#### a. Removal

(1) Refer to paragraph 3-6a(I) and (2) to remove chassis assembly from combination case and swing card cages open.

(2) Tag and remove wires from terminal board TB1. Note position of jumper strips before removing them.

(3) Remove six screws (84), flatwashers (85) screws (86), and flatwashers (87), remove two angle brackets (88)

(4) Remove four screws (89) and flatwashers (90)carefully lift plate (91) from heat exchanger.

(5) Remove four screws (101), locknuts(1.02)and flatwashers (103); remove terminal boardTB1(104)and marker strip (105) fromplate (91)

b. Replacement

(1) Attach marker strip (105) and terminal board TB1 (104) to plate (91) using four flatwashers (103), locknuts (102), and screws (101).

(2) Attach plate (91) to heat exchanger using four flatwashers (90) and screws (89).

(3) Install two angle brackets (88) using six flatwashers (87), screws (86), flatwashers (85), and screws (84).

(4) Install jumper strips in positions noted before removal and attach tagged wires to terminal board TB1.

(5) Refer to paragraph 3-6b(3) and (4) to secure card cages to chassis assembly and install chassis assembly in combination case.

3-23. Removal and Replacement of Bus Bars 2A1W2 and 2AIW3 (fig. 3-2)

a. Removal

(1) Refer to paragraph 3-6a(1) and (2) to remove chassis assembly from combination case and swing card cages open.

(2) Tag and remove wires from bus bars W2 and W3.

(3) Remove six screws (84), flatwashers (85), screws (86), flatwashers (87); remove two angle brackets (88).

(4) Remove four screws (89) and flatwashers (90); remove plate (91).

(5) Remove six screws (106), locknuts (107), and flatwashers (108); remove two bus bar retainers (109), bus bars W2 and W3 (110), and two bus bar brackets (111).

b. Replacement

(1) Attach two bus bar brackets (111), bus bars W2 and W3 (110), and two bus bar retainers (109) using six flatwashers (108), locknuts (107), and screws (106).

(2) Attach plate (91) to heat exchanger using four flatwashers (90) and screws (89).

(3) Install two angle brackets (88) using six flatwashers (87), screws (86), flatwashers (85), and screws (84).

(4) Attach tagged wires to bus bars W2 and W3.

(5) Refer to paragraph 3-6b('3) and (4) to secure card cages to chassis assembly and install chassis assembly in combination case.

#### 3-24. Removal and Replacement of Card Cage Connectors (fig. 3-2)

The following removal and replacement procedure applies to connectors J1 and J2 of all card cages in the SCU and LCU. It is assumed in this procedure that access to the card cage has been made.

#### a. Removal

(1) Remove circuit cards from card cage (TM 11-6626-2441-12).

(2) Loosen two connector retaining screws (112) and carefully disconnect two mating connectors (113).

(3) Tag and remove wires and contacts from damaged connector. (Refer to paragraph 3-47 for proper contact removal tool.)

(4) Remove two screws (114), nuts (115), lockwashers (116), and flatwashers (117); remove connector (1 18).

#### b. Replacement

(1) Attach connector (118) to card cage using two flatwashers (117), lockwashers (116), nuts (115), and screws (114).

(2) Insert tagged wires and contacts in connector. (Refer to paragraph 3-2ce for proper insertion tool.)

(3) Connect two connectors (113) and tighten two connector retaining screws (112).

(4) Install circuit cards (TM 11-66252441-12).

(5) Install chassis assembly in combination case.

#### 3-25. Removal and Replacement of Connector Plate (fig. 3-2)

The following removal and replacement procedure applies to the connector plate of all SCU and LCU card cages. It is assumed in this procedure that access to the card cage has been made.

a. Removal

(1) Remove all circuit cards from card cage with damaged connector plate (TM 11-6625-2441-12).

(2) Loosen two or four captive screws (3) and swing card cage(s) out.

(3) Remove six screws (119) and flatwashers (120); remove six spacers (121) and cover 1122).

(4) Tag and remove wires from standoffs E1 and W1 (123).

(5) Loosen two connector retaining screws (112) and disconnect two connectors (113).

(6) Remove four screws (114), nuts !115;), lockwashers (116), and flat. washers (117); remove connectors JI and J2 (118). Do not remove wires and contacts from connectors.

(7) Remove 13 screws (124). lockwashers (125), flatwashers (126), and bushings (127); remove connector plate assembly (128), spacer (129), two spacers (130), and four spacers (131).

b. Replacement

(1) Attach four spacers (131), two spacers (130), spacer (129), and connector plate assembly (128) to card cage frame using 13 bushings (127), flatwashers (126), lockwashers (125), and screws (124).

(2) Install connectors JI and J2 (118) using four flatwashers (117), lockwashers (116), nuts (115), and screws (114).

(3) Connect two connectors (113) and tighten two connector retaining screws (112).

(4) Route tagged wires through grommet in card cage and attach to standoffs W1 and E1 (123).

(5) Attach cover (122) to card cage using six spacers (121), flatwashers (120), and screws (119).

(6) Swing card cage(s) back to normal position; secure to chassis assembly by tightening captive screws(3).

3-17

- (7) install chassis assembly in combination
  - 3-26. Removal and Replacement of Card Cage 2A1A3 (fig. 3-2)
- a. Removal

(1) Refer to paragraph 3-6a(1) to remove chassis assembly from combination case.

(2) Remove circuit cards (TM 11-6625-2441-12).

(3) Loosen two connector retaining screws (112) and carefully disconnect two connectors (113).

(4) Loosen ,two captive screws (3) and swing card cage A3 (135) open.

(5) Remove six screws (119) and flatwashers (121)): remove, sax spacers (121) and cover (122).

(6) Tag and remove Wires from standoffs E1 and W1 (123)

(7) Drive two pins (132) from hinge posts; remove two hinge pins (133),nylon. shim washers (132), and card cage A3 (135).

## NOTE

Nylon shim washers are used to reduce the end play of card cage hinge assemblies. Assemblies may have one. two, or no nylon shims installed. When removing a card cage, note the quantity and the position of the shims relative to the card (age: install shims in the same quantity and in the same position when replacing the card cage.

b. Replacement

(1) Remove six screws (119) and flatwashers (120): remove six spacers (121) and (-over (122) from replacement card cage.

(2) Attach card cage A'l3 (135) to chassis assembly with nylon shim washer(s) (134, in the same position and quantity noted in removal), two hinge pins (133), and two pins (132).

(3) Connect two connectors (113) to J1 and J2 (118) and tighten two connector retaining screws (112).

(4) Route tagged wires through grommet in card cage and attach to standoffs WI and E1 (123).

(5) Attach cover (122) to card cage using six spacers (121), flatwashers (120), and screws (119).

(6) Secure card cage to chassis assembly using two captive screws (3).

(7) Install circuit cards (TM 11-6625-2441-12).

(8) Refer to paragraph 3-6b(4) to install chassis assembly in combination case.

## 3-27. Removal and Replacement of Card Cages 2A1A1, 2A1A2, and 1A1A1 through 1A1A4 (fig. 3-2)

The following removal and replacement procedures are applicable to card cages in both the LCU and SCU. It shall be assumed that the chassis assembly has been removed from the combination case. When removing card cage 1A1A3 or 1A1A4 from the LCU, it is necessary to swing the card cage assembly away from the chassis assembly (TM 11-6625-2441-12).

a. Removal. Steps (2) through (5) below apply to the card cage to be replaced and the adjacent card cage. Steps (7) through (9) apply to the card cage being replaced only.

(1) Remove circuit cards from damaged card cage (TM 11-6625-2441-12).

(2) Looser four captive screws (3) and swing card cages clear.

(3) Remove 12 screws (119) and flatwashers (120); remove 12 spacers (121) and two covers (122).

(4) Remove four screws (136), lockwashers (137), flatwashers (138), and bushings (139); remove two ground straps (140).

(5) Remove six screws (141) and flatwashers (142); remove three connecting plates (143). (One connecting plate is located on the connector end of the card cage, the other two on the opposite end.)

(6) Swing good card cage into normal position and secure using captive screw (3).

(7) Tag and remove wires from standoffs E1 and W1 (123).

(8) Loosen two connector retaining screws (112) and disconnect two connectors (113).

(9) Remove two pins (144) and remove hinge pin (145), nylon shim washer(s) (146), and card cage (147).

## NOTE

Nylon shim washers are used to reduce the end play of card cage hinge assemblies. Assemblies may have one, two, or no nylon shims installed. When removing a card cage, note the quantity and the position of the shims relative to the card cage; install shims in the same quantity and in the same position when replacing the card cage.

#### b. Replacement

(1) Remove six screws (119) and flatwashers (120); remove six spacers (121) and cover (122) from replacement card cage.

(2) Attach card cage (147) to chassis assembly hinge posts with nylon shim washer(s) (146, in the same position and quantity noted in removal), hinge pin (145), and two pins (144).

(3) Connect two connectors (113) to mating card cage connectors and tighten two connector retaining screws (112).

(4) Attach tagged wires to standoffs W1 and El (123). Route wires through grommet in card cage.

(5) Loosen captive screw (3) and swing card cage out and align with replacement card cage. (Refer to a(6) above.)

(6) Connect the two card cages using three connecting plates (143), six flatwashers (142), and screws (141).

(7) Attach two ground straps (140) to card cages using four bushings (139), flatwashers (138), lockwashers (137), and screws (136). To attach the ground strap, it will be necessary to remove the required hardware from the replacement card cage.

(8) Install two covers (122) using 12 spacers (121), flatwashers (120), and screws (119).

(9) Swing card cages into proper position and secure using four captive screws (3).

(10) Install circuit cards in card cage (TM 11-6625-2441-12).

(11) Refer to the appropriate paragraph and install the chassis assembly in the combination case.

3-28. Removal and Replacement of indicators 1A1A5DS] through 1A1A5DS6 and 1AIA5DS9 (fig. 3-3)

a. Removal

(1) Loosen 12 stud nuts (1) that secure chassis assembly (2) to combination case and remove chassis assembly from combination case.

(2) Loosen seven captive screws that secure the two halves of the chassis assembly and swing chassis assembly open.

(3) Tag and unsolder wires attached to terminals of faulty indicator.

(4) Remove two screws (3) that secure legend plateholder (4), legend plate (5), and gasket (6) to front panel IAIA5 (7).

(5) Remove two screws(8), washers (9), and mounting bushings E1 that secure indicator base and spacer (11) to back of front panel.

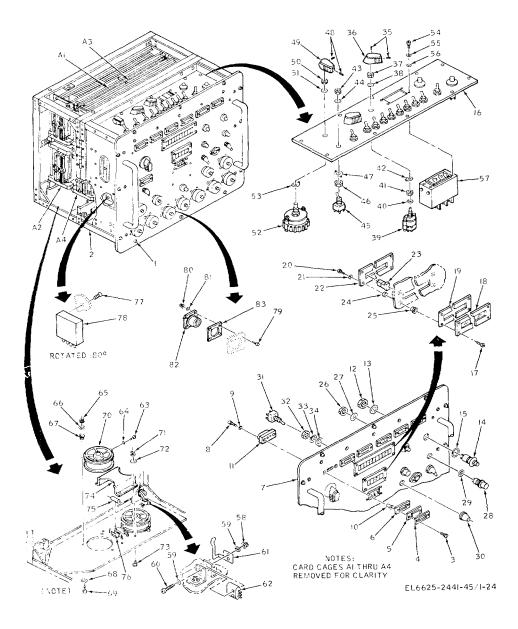


Figure 3-3. Logic Control Unit TS-2912/ASM-386 exploded view

1 Stud nut (12) 2 Chassis assembly 3 Screw (14) 4 Legend plateholder (7) 5 Legend plate (7) 6 Gasket (7) 7 Front panel 1AIA5 8 Screw (14) 9 Washer (14) 10 Mounting bushing (14) 11 Indicator base and spacer (7) 12 Nut (5) 13 Lockwasher (5) 14 Switch (5; 1AIA5S2, 1ATA5S3, IAIA6S5, 1A1A6S6, IAIA5S8) 15 Seal (5) 16 Test panel 1AIA6

- 17 Screw (8) 18 Bezel and neutral density filter assembly (2) 19 Gasket (2) 20 Screw (8) 21 Washer (8) 22 Mounting strip (2) 23 Lamp assembly (15) 24 Spacer (8) 25 Mounting collar (8) 26 Nut (2) 27 Lockwasher (2) 28 Indicator (2, IAIA5DSIU and 1A1A5DS11) 29 O-ring (2) 30 Boot (3) 31 Switch (3; 1AIA5S4, 1AIA5S6, IAIA5S7) 22 Nut (2)
- 32 Nut (3)
- 33 Lockwasher (3)

34 Keywasher (3) 35 Setscrew (6) 36 Knob (3) 37 Nut (3) 38 Lockwasher (3) 39 Switch (3; IAiA5S1, IAIA6S2, IA1A6S3) 40 0-ring (3) 41 Nut (3) 42 Keywasher (3) 43 Nut (11) 441 Loc.'-washer (11) 45 Switch (11, IAIA6S7 through 1AIA6SI7) 16 Nut (11) 47 Keywasher (i1) 48 Setscrew (2) 49 Knob 50 Nut 81 Lockwasher 52 Switch I AIA6S1 53 Keywasher 54 Screw (8) 55 Lockwasher (8) 56 Washer (8) 57 Thumbwheel switch (2, IAIA6S4 and 1AIA5S5) 58 Nut (2)

#### b. Replacement

(1) Attach indicator base and spacer (11 to back of front panel 1A1A5 (7) using two mounting bushings (10), washers (9), and screw (8).

(2) Solder tagged wires to proper terminals of replacement indicator.

(3) Attach gasket (6), legend plate (5) and legend plateholder (4) to front panel 1A1A5 (7) with two screws (3).

(4) Close two halves of chassis assembly and tighten seven captive screws.

(5) Slide chassis assembly (2) into combination case and tighten 12 stud nuts (1).

# 3-29. Removal and Replacement of Switches 1A1A5S2, 1A1A5S3, 1A1A.5S8, 1A1A6S5' and 1A1A6S6 (fig. 3-3)

The following removal and replacement procedures apply to front panel switches S2, S3' and S8 and test panel switches S5 and S6.

# a. Removal

(1) Refer to paragraph 3-21/2'i(1) and (2 to remove chassis assembly from combination case and to open chassis assembly.

59 Washer (4) 60 Screw (2) 61 Actuator 62 Panel lockout switch IAIS1 63 Screw (6) 64 Washer (6) 65 Nut (6) 66 Washer (6) 67 Cleat (6) 68 Washer (6) 69 Screw (6) 70 Blower (2, 1A1B1 and 1A1B2) 71 Nut (4) 72 Washer (4) 73 Screw (4) 74 Capacitor cover 75 Capacitor (2, 1A1C1 and 1A1C2) 76 Clip (2) 77 Screw (2) 78 Oscillator 1A1Y1 79 Screw (44) 80 Nut (44) 81 Flatwasher (44) 82 Connector(11, 1A1J1 through 1A1J11) 83 Emi gasket (11)

(2) Tag and unsolder wires from faulty switch terminals.

(3) Remove nut (12) and lockwasher (13) that secure switch (14) and seal (15) to front panel 1A1A5 (7) or test panel 1A1A6 (16); remove switch and seal.

b. Replacement

(1) Place seal (15) and switch (14) in front panel 1A1A5 (7) or test panel 1A1A6 (16) and secure with lockwasher (13) and nut (12).

(2) Solder tagged wires to proper terminals of replacement switch.

(3) Refer to 3-28b(4) and (5) to secure chassis assembly halves and install chassis assembly in combination case.

# 3-30. Removal and Replacement of Digital Display Indicators 1A1A5DS7 and 1A1A5DS8 (fig. 3-3)

a. Removal

(1) Refer to 3-28a(1) and (2) to re-move chassis assembly from combination case and to open chassis assembly.

(2) Tag and unsolder wires from faulty digital display indicator lamp assembly.

(3) Remove four screws (17); remove bezel and neutral density filter assembly (18) and gasket (19) from front panel IAIA5 (7).

(4) Remove four screws (20) and washers (22-1); remove mounting strip (22) and lamp assembly (23) and four spacer (24) and mounting collars, from front panel 1A1A5 (7).

#### b Replacement

(1) Secure four mounting collars (25) and spacers (24) and lamp assembly (23) and mounting strip (22) to rear of front panel 1A1A5 (7) with four washers (21) and screws 20).

(2) Secure gasket (19) and bezel and neutral density filter assembly (18) to front panel 1A1A5 (7) with four screws (17).

(3) Solder tagged wires to proper terminals o-f replacement digital display indicator.

(4) Refer to 3-28b(4) and (5) to secure chassis assembly halves and install chassis assembly in combination case.

## 3-31. Removal and Replacement of Indicators 1A1A5DS10 and 1A1A5DS11 (fig. 3-3)

#### a. Removal

(1) Refer to 3-28a(1) and (2) to remove chassis assembly from combination case and to open chassis assembly.

(2) Tag and unsolder wires attached to terminals of faulty indicator.

(3) Remove nut (26) and lockwasher (27); remove indicator (28) and 0-rirg (29) from front panel 1A1A5 (7).

#### b. Replacement

(1) Replace 0-ring (29) and indicator (28) on front panel 1A1A5 (7) using lockwasher (27) and nut (26).

(2) Solder tagged wires to proper terminals of replacement indicator.

(3) Refer to 3--28b(4) and (5) to secure chassis assembly halves and install chassis assembly in combination case.

**3-32. Removal and Replacement** of in-witches 1A1A5S4, 1A1A556, and IAIASS7 (fig. 3-3)

#### a. Removal

(1) Refer to 328a (1) and (2), to remove chassis assembly, from combination case and to open chassis assembly.

(2) Tag and unsolder wires from terminals of faulty switch.

(3) Remove boot (30), remove switch (31), nut (32). lockwasher (33), and keywasher (34) from front panel 1A1A15 (7)

b. Replacement

(1) Attach keywasher (31,),  $\P$  (33), nut (32) and switch (31) to front panel 1A1A5 (7) using boot (30); tighten nut (32).

(2) Solder tagged wires to proper terminals of replacement switch.

(3) Refer to 3--28b(4) and (5) to secure chassis assembly halves and install chassis assembly in combination case.

## 3-33. Removal and Replacement of Switches 1A1A5S1, 1A1A6S2, and 1A1A6S3 (fig. 3-3)

The following removal and for placement procedure applies to front panel switch S1 and test panel switches S2 and S3.

#### a. Removal

(1) Refer to 3–28a(1) and (2) to remove chassis assembly from combination case and to open chassis assembly.

(2) Tag and unsolder wires attached to terminals of faulty switch.

(3) Loosen two setscrews (35) that secure knob (36) to switch.

(4) Remove nut (37) and lockwasher (38); remove switch (39), 0-ring (40), nut (41), and keywasher (42) from front panel IAIA5 (7) or test panel IAIA6 (16).

#### b. Replacement

(1) Attach keywasher (42), nut (41), 0ring (40), and switch (39) to front panel IAIA5 (7) or test panel 1A1A6 (16) with lockwasher (38) and nut (37).

(2) Solder tagged wires to proper terminals of replacement switch.

(3) Secure knob (36) to switch with two setscrews (35).

(4) Refer to 3-28b(4) and (5) to secure chassis assembly halves and install chassis assembly in combination case.

3-34. Removal and Replacement of Switches 1AIA6S7 through 1A'IA6S17 (fig. 3-3)

a. Removal

(1) Refer to 3-28a(1) and (2) to remove chassis assembly from combination case and to open chassis assembly.

(2) Tag and unsolder wires attached to terminals of faulty switch.

(3) Remove nut (43) and lockwasher (44); remove switch (45), nut (46), and keywasher (47) from test panel 1A1A6 (16).

## b. Replacement

(1) Attach keywasher (47), nut (46), and switch (4.5; to, test panel t.'iA6 (16) with lockwasher (44) and nut (43).

(2) Solder tagged wires to proper terminals of replacement switch.

(3) Refer to 3-28b(4) and (5) to secure chassis assembly halves and install chassis assembly in combination case.

## 3-35. Removal and Replacement of Switch

1A1A6S1 (fig. 3 -3)

a. Removal

(1) Refer to 3-28a(1) and (2) to remove chassis assembly from combination case and to open chassis assembly.

(2) Tag and unsolder wires attached to terminals of switch S1.

(3) Loosen two setscrews (48) that secure knob (49) to switch S1.

(4) Remove nut (50) and lockwasher (51); remove switch SI (52) and keywasher (53) from test panel IAIA6 (16).

#### b. Replacement

(1) Attach keywasher (53) and switch SI (52) to test panel IAIA6 (16) with lockwasher (51) and nut (50).

(2) Solder tagged wires to proper terminals of switch S1.

(3) Secure knob (49) to switch SI with two setscrews(48).

(4) Refer to 3-28b(4) and (5) to secure chassis assembly halves and install chassis assembly in combination case.

## 3-36. Removal and Replacement of Thumbwheel Switches 1A1A6S4 and 1A1A5S5 (fig. 3-3)

The following removal and replacement procedure applies to test panel thumbwheel switch S4 and front panel thumbwheel switch S5.

a. Removal

(1) Refer to 3-28a(1) and (2) to remove chassis assembly from combination case and to open chassis assembly.

(2) Tag and unsolder wires attached to terminals of faulty thumbwheel switch.

(3) Remove four screws (54), lockwashers (55), and washers (56); remove thumbwheel switch (57).

# b. Replacement

(1) Attach thumbwheel switch (57) to panel with four washers (56), lockwashers (55) and screws (54).

(2) Solder tagged wires to proper terminals of replacement thumbwheel switch.

(3) Refer to 3--28b(4) and (5) to secure chassis assembly halves and install chassis assembly in combination case.

## 3-37. Removal and Replacement of Panel Lockout Switch 1A1S1 (fig. 3-3)

a. Removal (1) Refer to 3-28a(1) to remove chassis assembly from combination case.

(2) Loosen two captive screws that secure card cage 1A1A.,2 to rear half of chassis assembly and swing card cage 1AIA2 clear of blower interlock switch.

(3) Tag and unsolder wires attached to blower interlock switch SI.

(4) Remove two nuts (58), four washers (59), and two screws (60); remove actuator (61) and blower interlock switch S (62).

# b. Replacement

(1) Attach blower interlock switch SI (62) and actuator (61) to rear half of chassis assembly (2) with two screws (60), four washers (59), and two nuts (58).

(2) Solder tagged wires to proper terminals of blower interlock switch S1.

(3) Swing card cage 1A1A2 into position on rear half of chassis assembly (2) and tighten two captive screws.

(4) Refer to 3-28b(5) to install chassis assembly in combination case.

# 3-38. Removal and Replacement of Blower 1A1B1 and 1A1B2 (fig. 3-3)

a. Removal (1) Refer to 3-28a(1) and (2) to remove chassis assembly from combination case and to open chassis assembly.

(2) Loosen eight captive screws that secure card cages 1A1A1 through 1AIA4 to rear half of chassis assembly (2) and swing the four card cages clear of the rear half of the chassis assembly.

(3) Tag wires attached to faulty blower terminals; remove three screws (63) and washers (64) and wires.

(4) Remove three nuts (65), washers (66), cleats (67), washers (68), and screws (69); remove blower (70) from chassis assembly (2).

b. Replacement

(1) Secure blower (70) to chassis assembly (2) with three screws (69), washers (68), cleats (67), washers (66), and nuts (65).

(2) Attach wires to proper terminals of replacement blower and secure with three washer (64) and screws (63).

(3) Swing card cages 1A1A1 through IAIA4 into position on rear half of chassis assembly (2) and tighten eight captive screws.

(4) Refer to 3-28b(4) and (5) to secure chassis assembly halves and install chassis assembly in combination case.

3-39. and Replacement of Capacitors 1A1Cl and 1A1C2 (fig. 3-3)

(1) Refer to 3-28a(1) and (2) to remove chassis assembly from combination case and to open chassis assembly.

(2) Loosen eight captive screws that secure card cages 1A1A1 through 1A1A4 to

rear half of chassis assembly (2) and swing card cages clear of rear half of chassis assembly.

(3) Remove four nuts (71), washers (72), and screws (73); remove capacitor cover (74) from chassis assembly (2).

(4) Unsolder leads of capacitor (75) and remove from clip (76).

b. Replacement

(1) Place capacitor (75) in clip (76) and solder capacitor leads to standoff terminals.

(2) Attach capacitor cover (74) to chassis assembly (2) with four screws (73), washers (72), and nuts (71).

(3) Swing card cages IAIAI through IAIA4 into position on rear half of chassis assembly and tighten eight captive screws.

(4) Refer to 3-28b(4) and (5) to secure chassis assembly halves and install chassis assembly in combination case.

# 3-40. Removal and Replacement of Oscillator 1A1Y1 (fig. 33)

a. Removal

(1) Refer to 3-28a(1) and (2) to remove chassis assembly from combination case and to open chassis assembly.

(2) Tag and unsolder wires attached to leads of oscillator Y1.

(3) Remove two screws (77); remove oscillator Y1 (78) from chassis assembly (2).

b. Replacement

(1) Attach oscillator Y1 (78) to chassis assembly (2) with two screws (77).

(2) Solder tagged wires to proper terminals of oscillator Y1.

(3) Refer to 3-28b(4) and (5) to secure chassis assembly halves and install chassis assembly in combination case.

# 3-41. Removal and Replacement of Connectors 1A1J1 through 1A1J1 (fig. 3-3)

a. Removal

(1) Refer to paragraph 3-28a(1) and (2) to remove chassis assembly from combination case and to open chassis assembly.

(2) Tag and remove wires and contacts of connector.

(3) Remove four screws (79), nuts (80), and flatwashers (81); remove connector (82) and emi gasket (83).

b. Replacement

(1) Attach emi gasket (83) and connector (82) to front panel using four flatwashers (81), nuts (80), and screws (79).

(2) Insert tagged wires into connector.

(3) Refer to paragraph 3-28b(4) and (5) to secure chassis assembly halves and install chassis assembly in combination case.

# 3-42. Removal and Replacement of Connectors 3A4-2J1 through 3A4-2J8, 3A4-2JI5, 3A4-2J16, and 3A4-3J1 (fig. 3-4)

a. Removal

(1) Remove 14 screws (1) and flatwashers (2); remove cover (3) from chassis (4).

(2) Tag and remove wires from connector.

(3) Remove four screws (5), locknuts (6), and flatwashers (7) remove connector (8) and emi gasket (9)

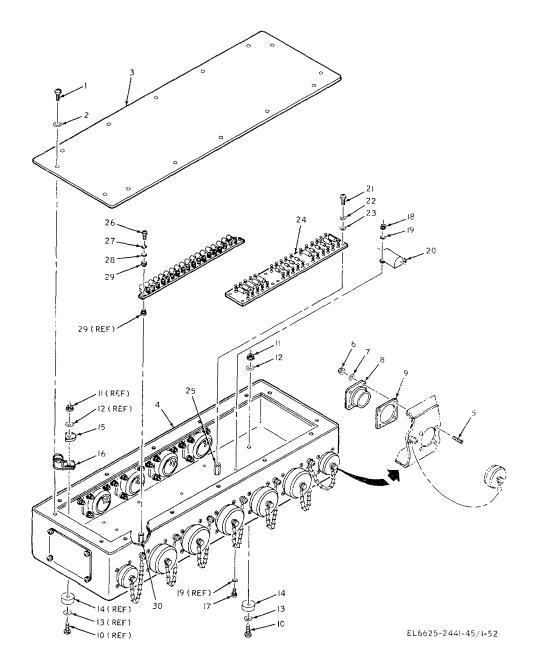


Figure 3-4. Adapter, Self-Test MX-8586/ASII-386 exploded view.

1 Screw (14) 2 Flatwasher (14) '3 Cover 4 Chassis 5 Screw (44) 6 Locknut (44) 7 Flatwasher (44) 8 Connector (11; 3A4-2J1 through 3A4-2J8, 3A4-2J15, 3A4-2J16, 3A4-3J1) 9 Emi gasket (11) 10 Screw (4) 11 Nut (4) 12 Flatwasher (4) 13 Flatwasher (4) 13 Flatwasher (4) 15 D-washer (3) 16 Cable clamp (3) 17 Screw (2) 18 Locknut (2) 19 Flatwasher (4) 20 Resistor 3A4R1 21 Screw (4) 22 Lockwasher (4) 23 Flatwasher (4) 24 Component board SA4AI 25 Standoff (4) 26 Screw, (2) 27 Lockwasher (2) 28 Flatwasher (2) 29 Shoulder washer (4) 30 Bus bar 3A4IWi 31 Spacer (2)

# b. Replacement

(1) Attach emi gasket (9) and connector (8) to chassis (4) using four flatwashers (7), locknuts (6). and screws (5).

(2) Attach tagged wires to connector.

(3) Attach cover (3) to chassis (4) using 14 flatwashers (2; and screws (1).

# 3-43. Removal and Replacement of Bumpers and Cable Clamps (fig 3-4)

Hardware used to attach the four bumpers to the self-test adapter also secure the three cable clamps.

a. Removal

(1) Remove 14 screws (1) and flatwashers (2); remove cover (3) from chassis (4).

(2) Remove four screws (10), nuts (11), flatwashers (12), and flatwashers (13); remove four bumpers (14), three D-washers (15), and three cable clamps (16) from chassis (4).

b. Replacement

(1) Attach three cable clamps (16), three Dwashers (1). and four bumpers (14) to chassis (4) using four flatwashers (13), flatwashers (12), nuts (11) and screws (10).

(2) Attach -over (3) to chassis (4) using 14 flatwashers (2) and screws (1).

# 3-44. Removal and Replacement of Resistor 3A4R1 (fig. 3-4)

a. Removal

(1) Remove 14 screws (1) and flatwashers (2); remove cover (3) from chassis (4).

(2) Unsolder wires from resistor R1 terminals.

(3) Remove two screws (17), two locknuts (18), and four flatwashers (19); remove resistor R1 (20) from chassis (4).

b. Replacement

(1) Attach resistor R1 (20) to chassis (4) using four flatwashers (19), two locknuts (18), and two screws (17).

(2) Solder wires to resistor RI terminals.

(3) Attach cover (3) to chassis (4) using 14 flatwashers (2) and screws (1) 3-45. Removal and Replacement of Component Board 3A4A1 (fig. 3-4)

3-45. a. Removal

(1) Remove 14 screws (1) and washers (2); remove cover (3) from chassis (4).

(2) Tag and unsolder wires from component board A1 terminals.

(3) Remove four screws (21), lockwashers (22), and flatwashers (23); remove component board Al (24) from four standoffs t25).

b. Replacement

(1) Attach component board Al (24) to four standoffs (25) using four flatwashers 123), lockwashers (22), and screws (21).

(2) Solder tagged wires to component board AI terminals.

(3) Attach cover (3) to chassis (4) using 14 flatwashers (2) and screws (1).

# 3-46. Removal and Replacement of Bus Bar 3A4W1 (fig. 3-4)

a. Removal
(1) Remove 14 screws (1) and flatwashers
(2); remove cover (3) from chassis (4).

3-27

(2) ;and remove wires from bus bar W1

(3) Remove two screws (26), two lockwashers(27), two flatwashers (28), and four shoulder washers (29); remove bus bar W1 (30) from two standoffs (31).

b. Replacement

(1) Attach bus bar W1 (30) to two standoffs (31) using four shoulder washers (29). two flatwashers (28), two lockwashers (27), and two screws (26).

(2) Attach tagged wires to bus bar W1

(3) Attach cover (3) to chassis (4) using 14 flatwashers (2) and screws (1).

# 3-47. Connector Repair and Replacement (fig. 3-5, 3-6, and 5-9)

The procedures in this paragraph are for test set connectors that are not military standard connectors. These procedures may also b)e used for connector repair. The following chart lists the recommended contact removal and insertion tool and contact locator head for each connector. The contact locator heads listed are used with the MH750 crimping tool. Equivalent tools may be substituted for the tools listed.

#### CAUTION

The proper tool is determined by the contact size. Do not use the wrong tool.

## NOTE

Removal and replacement procedures are the same for both connector pins and sockets.

connector	Contact removal tool (manufacturer	Contact inspection tool (manufacturer)	contact locator head (Daniels)
CONNECTOR	tool (manufacture)		neau (Danieis)
1A1A1A31J1	TWO22RT000 (Hughes)	TWO22IT000 (Hughes)	P6
1A1A1A31J2	TWO22RT000 (Hughes)	TWO22IT000 (Hughes)	P6
1A1A1A31J1	TWO22RT000 (Hughes)	TWO22IT000 (Hughes)	P6
1A1A1A31J2	TWO22RT000 (Hughes)	TWO22IT000 (Hughes)	P6
1A1A1A31J1	TWO22RT000 (Hughes)	TWO22IT000 (Hughes)	P9
1A1A1A31J2	TWO22RT000 (Hughes)	TWO22IT000 (Hughes)	P6
1A1A1A31J1	TWO22RT000 (Hughes)	TWO22IT000 (Hughes)	P6
1A1A1A31J2	TWO22RT000 (Hughes)	TWO22IT000 (Hughes)	P6
1A1A5P1	TWO22RT000 (Hughes)	TWO22IT000 (Hughes)	P6
1A1A6P1	TWO22RT000 (Hughes)	TWO22IT000 (Hughes)	P6
1A1J4	11-8794-24 (Bendix)	11-8795-24 (Bendix)	P6
1A1J5	11-8794-24 (Bendix)	11-8795-24 (Bendix)	P6
1A1J112	TWO22RT000 (Hughes)	TWO22IT000 (Hughes)	P6
1A1J113	TWO22RT000 (Hughes)	TWO22IT000 (Hughes)	P6
1A1P1	TWO22RT000 (Hughes)	TWO22IT000 (Hughes)	P6
1A1P2	TWO22RT000 (Hughes)	TWO22IT000 (Hughes)	P6
1A1P3	TWO22RT000 (Hughes)	TWO22IT000 (Hughes)	P6
1A1P4	TWO22RT000 (Hughes)	TWO22IT000 (Hughes)	P6
1A1P5	TWO22RT000 (Hughes)	TWO22IT000 (Hughes)	P6
1A1P6	TWO22RT000 (Hughes)	TWO22IT000 (Hughes)	P6

Contact

Connector	Contact removal	Contact insertion	locator
Connector	tool (manufacturer)	tool (manufacturer)	head (Daniels)
1A1P7	TW022RT000 (Hughes)	TW022IT000 (Hughes)	P6
1A1P8	TW022RT000 (Hughes)	TW022IT000 (Hughes)	P6
2A1A1A31J1	TW022RT000 (Hughes)	TW022IT000 (Hughes)	P6
2A1A1A31J2	TW022RT000 (Hughes)	TW022IT000 (Hughes)	P6
2A1A2A31J1	TW022RT000 (Hughes)	TW022IT000 (Hughes)	P6
2A1A2A31J2	TW022RT000 (Hughes)	TW022IT000 (Hughes)	P6
2A1A3A31J1	TW022RT000 (Hughes)	TW022IT000 (Hughes)	P6
2A1A3A31J2	TW022RT000 (Hughes)	TW022IT000 (Hughes)	P6
2A1J3	11-8794-24 (Bendix)	11-8795-24 (Bendix)	P14
2A1J4	11-8794-24 (Bendix)	11-8795-24 (Bendix)	P14
2A1P1	TW022RT000 (Hughes)	TW022IT000 (Hughes)	P6
2A1P2	TW022RT000 (Hughes)	TW022IT000 (Hughes)	P6
2A1P3	TW022RT000 (Hughes)	TW022IT000 (Hughes)	P6
2A1P4	TW022RT000 (Hughes)	TW022IT000 (Hughes)	P6
2A1P5	TW022RT000 (Hughes)	TW022IT000 (Hughes)	P6
2A1P6	TW022RT000 (Hughes)	TW022IT000 (Hughes)	P6
3W9P1	11-8794-24 (Bendix)	11-8795-24 (Bendix)	P15
3W9P2	11-8794-24 (Bendix)	11-8795-24 (Bendix)	P15
3W10P1	11-8794-24 (Bendix)	11-8795-24 (Bendix)	P15
3W10P2	11-8794-24 (Bendix)	11-8795-24 (Bendix)	P15

a. The following procedure is applicable to special cable assembly nonmilitary standard purpose 3-5 connectors. Figure illustrates a typical configuration of this type connector. Figure 3-6 illustrates the configuration of banana tip plug 2W6P2. Use standard maintenance practices when replacing connector 2W6P2.

(1) Removal of bayonet coupling connectors

(a) Remove two cable clamp screws and unscrew cable clamp.

(b) Unscrew connector backshell and slide clear of connector shell.

(c) Tag connector contacts; using proper contact removal tool, carefully remove contacts (pins or sockets) by pushing out of connector insert from contact side of connector.

(2) Replacement of bayonet coupling connector

(a) Using proper contact insertion tool, carefully push contact into connector until contact is felt to snap into place. Use nylon plugs provided with connectors to fill all unused connector contact holes.

(b) Screw backshell on connector shell. Use caution when tightening backshell to prevent strain on contacts and wires.

(c) Screw cable clamp on backshell and secure with two cable clamp screws.

b. The following procedures are applicable to LCU and SCU harness connectors and their mating connectors. The tools listed in chart above are to be used for both pins and sockets.

(1) Tag each wire; using proper contact removal tool, carefully but firmly push contacts through connector from connector face.

(2) When replacing card cage connectors, refer to paragraph 3-24 for removal and replacement procedures

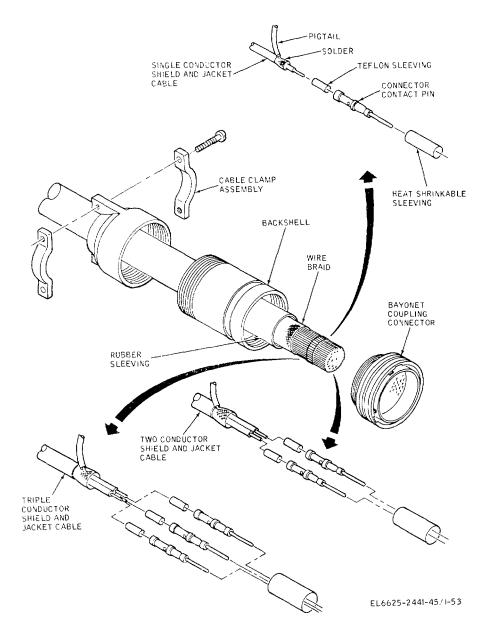


Figure 3-5. Special propose electrical cable assembly, typical shielded cable configuration and connector removal diagram.

(3) Grip tagged contact and wire with proper contact insertion tool and push firmly but carefully until contact is felt to snap into place.

c. The following procedures are applicable to connectors utilizing Termi-Point connections.

(1) Loading Termi--Point service tool (fig.3-

7)

(a) Remove spring clip from reel holder spindle.

(b) Place reel of clips on spindle with label side out and replace reel holder spindle spring clip.

(c) Pivot clip train protector down and feed clip train onto clip track.

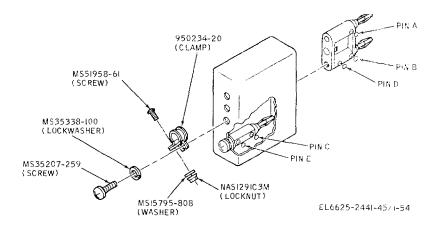


Figure 3-6. Connector 2W6P2, configuration diagram

(d) Using A-end of multipurpose tool, slide feed clip train along clip guide track until clip train stops at feed pawl.

(e) Using B-end of multipurpose tool, depress feed pawl and advance clip train until feed pawl engages the space between the first and second clips.

(f) Pivot clip train protector up and snap into place.

(2) Removing clips and wires (fig. 3-8)

(a) Hold extractor-locator tool perpendicular to connector and hook lip of extractor end of tool as shown. If replacing pin, remove all clips and wires. If repairing wiring harness, remove the clip and wire to be replaced.

(b) Twist tool clockwise to remove clip and wire. If replacing one or two clips, use locator end of tool to reposition remaining clips on connector pin.

(3) Preparation for use (fig. 3-9)

(a) Set clip position control to proper position.

(b) Use K. Miller model 100 wire stripper to cut wire to ensure wire end is not flattened. Do not strip wire.

(c) Insert unstripped wire into hole between resizer and mandrel, and push wire until it bottoms.

(d) Squeeze tool handle and release to ready clip and wire e for application to connector pin.

(4) Application (fig. 3-10)

#### CAUTION

If excessive resistance is encountered during application, do not exert excessive pressure; pin damage will occur.' Remove tool and begin application procedure again.

(a) Position Termi-Point tool so connector pin fits into exposed clip.

(b) Align tool vertically and horizontally and rest alignment foot on surrounding pins.

(c) Apply light pressure on tool until clip reaches preset position on post. Insure that pressure is straight toward connector pin.

(d) Remove tool, release handle and reset tool by pushing clip train protector fully forward.

(e) Depress insulation ejector to remove insulation from tool.

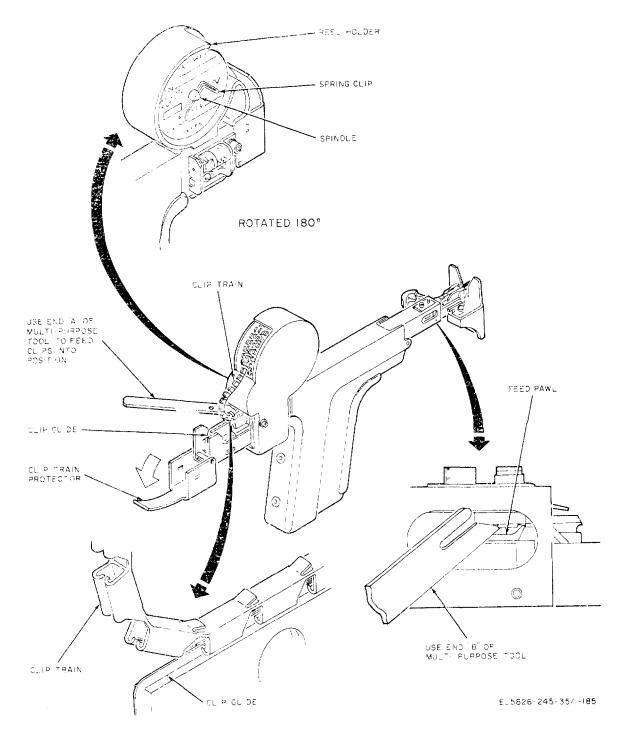


Figure 3-7. Termi-Point service tool loading.

3-32

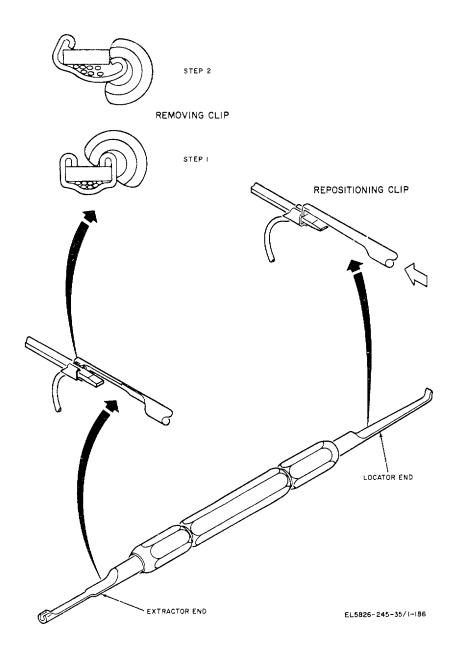
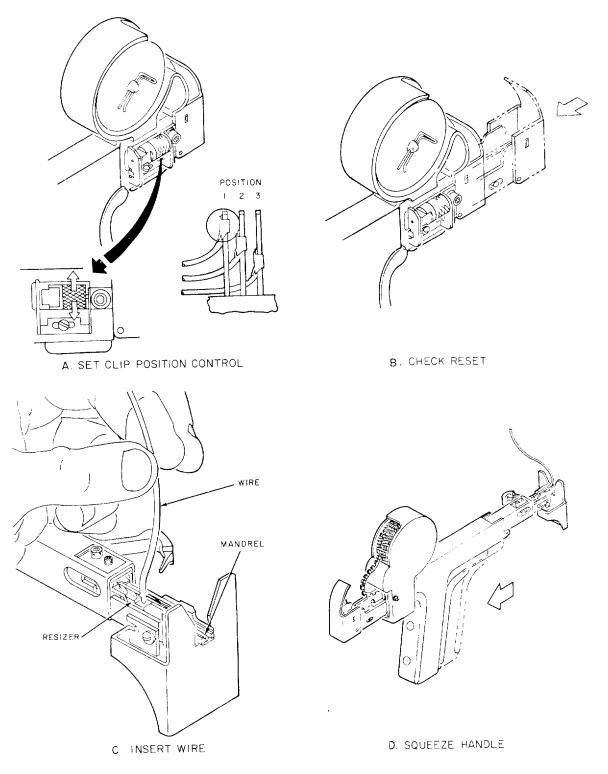


Figure 3-8. Extractor-locator tool.



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Figure 3-9. Preparing Termi-Point service tool for use.

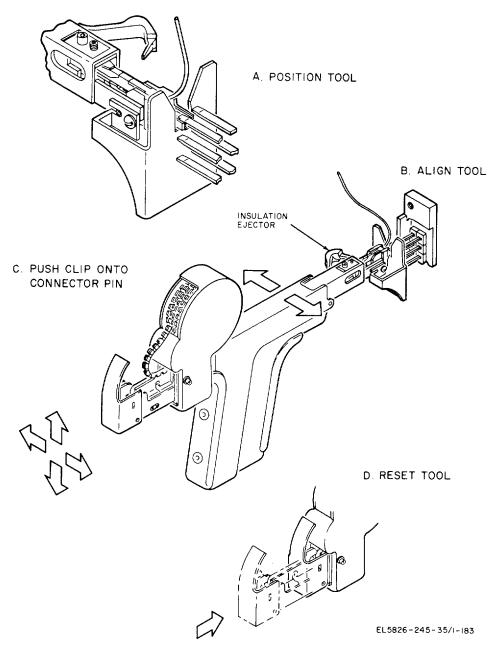


Figure 3-10. Applying clop to connector pin.

3-35

## **CHAPTER 4**

# **DEPOT MAINTENANCE**

Section I. GENERAL

## 4-1. Scope of Depot Maintenance

# Depot maintenance consists of testing, adjusting, and troubleshooting power supply 2AIPS1, rebuilding special purpose electrical cable assemblies, and complete overhaul of the test set. Procedures in this chapter also provide instructions for removal and replacement of discrete components and modules of power supply 2AIPS1. The procedures in this chapter combined with those in chapter 3 of this manual provide instructions for rebuilding the test set.

# 4-2. Tools, Test Equipment, and Materials Required

Tools, test equipment, and materials required, in addition to those listed in TM 11-6625-2441-12 and chapter 3 of this manual, are listed below.

a. Tools. The only additional tool required for depot maintenance is a precision oven, FSN 6640-531-4358, which provides controlled heat for curing epoxy adhesive.

b. Test Equipment. The following chart lists the test equipment required for depot maintenance.

Item	Part no. and manufacturer	Use
Test fixture, NCCITS power supply	TE 209316 (Litton)	Provides connections for excitation, variable and fixed loads, and test points for testing and adjusting power supply 2AIPS1
Power supply, dual dc	TW 5005 (Power Design)	Provides fixed +28 V excitation and variable test voltages for testing and adjusting power su 2AIPS1

c. Materials. The following chart lists the materials required for depot maintenance.

Material	FSN, federal specification or military specification	Use
Adhesive, epoxy, resin, metal-to-metal structural bonding	MIL-A-8623, Type I	Bonds metal to metal

Material	FSN, federal specification or military specification	Use
Insulating and sealing compound, electrical	MIL-I-8660	Provides additional heat conduction for power diodes and transistors
Capacitor, electrolytic, tantalum, solid (56 μF, 15 V)	MIL-C-39003	Provides filtering for filtered +4.7 V during power supply test

# Section II. TROUBLESHOOTING

# 4-3. General

Troubleshooting at depot maintenance consists of performing a close visual inspection of the equipment received from lower levels of maintenance and performing the procedures contained in this section. It shall be assumed that the items of equipment received at depot maintenance contain faulty components or modules. When performing the procedures in this section, care should be taken to prevent further damage to the equipment.

# 4-4. Power Supply 2AIPS1 Fault Isolation

Isolation to faulty discrete components or modules in the power supply is performed in two basic operations: a visual inspection and a functional test. Before performing the functional test, perform a careful visual inspection to locate any broken or burned components or wires. Replace faulty components or modules; removal and replacement procedures are located in paragraphs 4-9 through 4-37. If faulty wires, components, or modules are not found during the visual inspection, perform the procedures in paragraph 4-5.

## WARNING

The power supply contains voltages which may cause DEATH or SERIOUS INJURY. Be careful when taking readings or making adjustments in the power supply.

## CAUTION

Some of the power supply adjustments are very close to exposed terminals and pins. Use extreme care when making adjustments to prevent damage to the power supply.

## 4-5. Power Supply 2AIPS1 Test Procedure

## a. Preliminary Test Procedures

(1) Insure that all primary power to the NCCITS power supply test fixture (test fixture) is off.

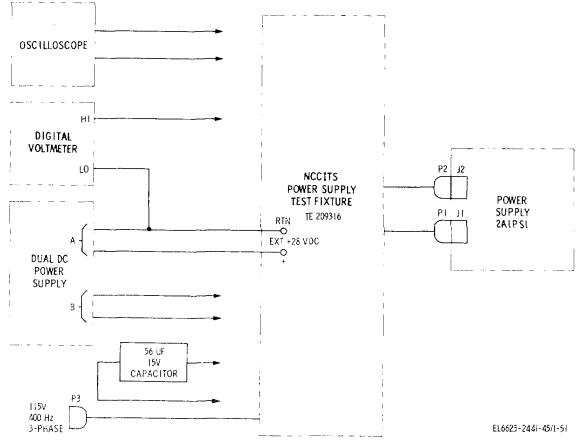
(2) Set test fixture switches and controls in as follows:

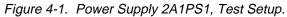
Switch or control	Position or
115 VAC switch	OFF
AUX AC switch	OFF
AC POWER switch	OFF
AUX 28V switch	OFF
+5V LOAD switch 4-2	NOM

Switch or control	Position or setting	
-15V LOAD switch	NOM	
-25V LOAD switch	NOM	
AUX 4.7V LOAD switch	RATED	
+28V LOAD switch	RATED	
FILTERED 4.7V LOAD switch	NOM	
RI control (multimeter connected between AUX 4.7 VDC test jack and EXT 28V RTN input jack)	Adjust R I for 9.4 ( $\pm$ 0.5) ohms	
R17 (multimeter connected between FILTERED 4.7 VDC test jack and EXT 28V RTN input jack)	Adjust R17 for 10.0 (, 0.5) ohms	
R19 (multimeter connected between +28 VDC test jack and EXT 28V RTN input jack)	Adjust R19 for 93 (, 2) ohms	
INTLK INPUT switch	OFF	
AUX 4.7V LOAD switch	NOM	
+28V LOAD switch	NOM	

# (3) Connect power supply and test fixture

(4) Turn on all external test equipment and





b. Test Procedures. Perform tests in the test procedure chart in the order listed. The Item column identifies the individual test to be performed. The Procedure column provides the step-by-step procedures and normal indication for each test. The Reference column locates the fault isolation and troubleshooting

procedures that are to be performed when tests result in abnormal indications.

NOTE

Unless otherwise specified, all controls, indicators, and jacks are located on the test fixture.

# c. Test procedure chart.

Sequence no.	ltem	Procedure	Reference
1	Power supply turnon	Apply primary power to power supply under test as follows:	Paragraph 4-7
		a Set dual dc power supply A output to +24.0 (±2.0) V	
		b. Set 115 VAC switch to ON	
		c. Simultaneously set AC POWER and AUX AC switches to ON	
		d. Observe the PS FAULT, VM NO-GO, +VCB, -VCB, and +5 VDC CB indicators are out	
		e. Connect DVM to the following test jacks and observe indica- tion of 0 (+O.5) Vdc:	
		<ul> <li>(1) FILTERED 4.7 VDC</li> <li>(2) +28 VDC</li> <li>(3) +5 VDC</li> <li>(4) +15 VDC</li> <li>(5) -15 VDC</li> <li>(6) -25 VDC</li> </ul>	
2	Auxiliary +4.7 V check	Connect digital voltmeter (DVM) and oscilloscope (scope) inputs to AUX 4.7 VDC test jack. Ob- serve the following: a DVM indicates +4.7 (+O.3) V	If voltage is out of tolerance refer to paragraph 4-39a. If voltage cannot be adjusted and/or ripple level is excessive, refer to paragraph 4-7.
		b. Ripple indication on scope less than 100 mV p-p	
3	Auxiliary +28 V check	Connect DVM and scope inputs to AUX 28V test jack. Observe the following:	Paragraph 4-7
		a. DVM indicates +28 (+2, -8) V	
		b. Ripple indication on scope less than 2000 mV p-p	
		4-4	

Sequence no.	Item	Procedure	Reference
4	Preparation for dc power on	<ul> <li>a. Connect 56-,uF, 15-V capacitor checks + terminal to FILTERED 4.7 VDC test jack and - terminal to EXT 28V RTN test jack</li> </ul>	
		b. Set AUX 28V switch to ON	
5	+28V	Connect DVM and scope inputs to +28 VDC test jack and observe the following: ripple level is excessive refer a. DVM indicates +28.00 (+0.05, to paragraph 4- -0.06) V	If voltage is out of tolerance refer to paragraph 4-39a If voltage cannot be adjusted and/or 7.
		b. Ripple indication on scope less than 300 mV p-p	
6	+15V check	Connect DVM and scope inputs to +15 VDC test jack and observe the following: ripple level is excessive, refer a. DVM indicates +15.00 (±0.03)V to paragraph 4	If voltage is out of tolerance refer to paragraph 4-39a. If voltage cannot be adjusted and/or -7.
		b. Ripple indication on scope less than 250 mV p-p.	
7	+5 V check	Connect DVM and scope inputs to +5 VDC test jack and observe the following: ripple level is excessive, refer a. DVM indicates +5.00 (+0.01 )V to paragraph 4	If voltage is out of tolerance, refer to paragraph 4-39a. If voltage cannot be adjusted and/or -7.
		b. Ripple indication on scope less than 100 mV p-p.	
8	Filtered +4.7 V	Connect DVM and scope inputs to FILTERED 4.7 VDC test jack and observe the following: ripple level is excessive, refer a. DVM indicates +4.70 (O.O1)V to paragraph 4-	If voltage is out of tolerance, refer to paragraph 4-39a. If voltage cannot be adjusted and/or
		b. Ripple indication on scope less than 100 mV p-p.	
9	-15 V check	Connect DVM and scope inputs to -15 VDC test jack and observe the following:	If voltage is out of tolerance, refer to paragraph 4-39a. If voltage cannot be adjusted and/or ripple level is excessive, refer to para-
		a DVM indicates -15.00 (±0.0) V	graph 47.
		b. Ripple indication on scope less than 250 mV p-p.	
10	-25 V check	Connect DVM and scope inputs to -25 VDC test jack and observe the following:	If voltage is out of tolerance, refer to paragraph 4-39a. If voltage cannot be adjusted and/or ripple level is excessive, refer
		a DVM indicates -25.00 (+0.05) V to paragraph 4	
		b. Ripple indication on scope less than 250 mV p-p.	

Sequence no.	ltem	Procedure	Reference
		Note: If PS FAULT indicator lights, set AUX AC switch to OFF and back to ON.	
11	Rated load checks	Set the following load switches to RATED	None
		a -25V LOAD	
		b15V LOAD	
		c. +15V LOAD	
		d +5V LOAD	
		e +28V LOAD	
		f FILTERED 4,7V LOAD	
12	+28 V check	Connect DVM and scope inputs to +28 VDC test jack and observe the following:	Paragraph 4-7
		a. DVM indicates +28 00 ( <u>+</u> 0.28) V7	
		b Ripple indication on scope less than 300 mV p-p	
13	+15 V check	Connect DVM and scope inputs to F15 VDC test jack and observe the following:	Paragraph 4-7
		a DVM indicates +15.00 ( <u>+</u> 015) V	
		b Ripple indication on scope less than 250 mV p-p	
14	+5 V check	Connect DVM and scope inputs to filter 2AIPS1FLIO and observe the following:	Paragraph -I-7
		a. DVMI indicates +5.00 ( <u>+</u> 0.15) V	
		b Ripple indication on scope less than 100 mV p-p	
15	Filtered <u>+</u> 4.7 V check	Connect DVM and scope inputs to filter 2AIPS1FLI2 and observe the following:	Paragraph 4-7
		a DVM indicates +4.70 (+0.14) V	
		<ul> <li>Ripple indication oi scope I less than 100 mV p-p</li> </ul>	

16	-15 V check	Connect DVM and scope inputs	Paragraph 4-7
		to -15 VDC test jack and observe the following:	
		a. DVM indicates -15.00 (+0.15) V	
		<ul> <li>Ripple indication on scope less than 250 mV p-p</li> </ul>	
17	-25 V check	Connect DVM and scope inputs to -25 VDC test jacks and observe the following:	Paragraph 4-7
		a. DVM indicates -25.00 ( <u>+</u> 0.25) V	
		<ul> <li>b. Ripple indications on scope less than 250 m V p-p</li> </ul>	
18	Voltage monitor circuit	Set all load switches to NOM	None
		Caution: When performing the checks in sequence no. 19 and 21, it is necessary to connect power supply out- puts to the EXT 28V RTN test jack (ground). To pre- vent serious damage to the power supply, do not hold connection for more than 0.5 seconds.	
19	Positive voltage monitor	Momentarily jumper +28 VDC no-go check input jack and observe the following:	Paragraph 4-7 test jack to EXT 28V RTN
		a. PS FAULT and VM NO-GO indicators light	
		<ul> <li>All power supply output voltages, except auxiliary +4.7 V and auxiliary +28 V, indicate 0 Vdc maximum</li> </ul>	
20	Power supply reset	Set AUX AC switch to OFF and back to on and ob- serve that PS FAULT and VM NO-GO indica- tors go out.	Paragraph 4-7
21	Negative voltage monitor	Momentarily jumper -25 VDC no-go check test jack to EXT 28V RTN input jack and observe the following:	Paragraph 4-7
		a. PS FAULT and VM NO- GO indicators light	

Sequence no.	ltem	Procedure	Reference
		<ul> <li>All power supply output voltages, except auxiliary +4.7 V and auxiliary +28 V, indicate 0 Vdc maximum</li> </ul>	
22	Preparation for power supply interlock check	Set AUX 28V, AC POWER, and AUX AC switches to OFF. Set AUX AC switch back to ON	None
23	Power supply interlock output check	Connect INTERLOCK OUT test jack to AC POWER ON test jack and observe that PS FAULT indicator goes out	Paragraph 4-7
24	Power supply interlock input check	Set INTLK INPUT switch to INTLK and observe that PS FAULT indicator lights	Paragraph 4-7
25	Preparation for crowbar checks	a. Set INTLK INPUT switch None to OFF	
		b. Remove jumper from INTERLOCK OUT and AC POWER ON test jacks	
		c. Set AUX AC and 115 VAC switches to OFF (all test fixture indica- tors go out)	
		d. Disconnect power supply from test fixture	
		e Remove wires from 2A1PS1A7 pin 6 (fig. 5-18). Leave wires connected together	
		f Connect power supply to test fixture (fig. 4-1)	
		g. Set 115 VAC, AUX AC, and AC POWER switches to ON Verify that power supply output voltages, except auxiliary +4.7 V and auxiliary +28 V, are o Vdc maximum	
		<ul> <li>h. Set all load switches to</li> <li>OFF and verify that AUX</li> <li>28 V switch is set to OFF</li> </ul>	
		Note: In sequence no. 26 through 31, the DVM indication must be monitored closely for sudden change.	
		4-8	

Sequence no.	ltem	Procedure	Reference
26	Positive voltage crowbar check (+28 V)	<ul> <li>a. Adjust dual dc power supply B output to 0 volts</li> <li>b Connect dual dc power supply B (+) output to +28 VDC test jack and (-) output to EXT 28V RTN input jack</li> </ul>	If voltage level in e is out of tolerance, refer to paragraph 4-39b. If voltage level cannot be adjusted or DVM indication is not as specified in d, refer to paragraph 4-7
		<ul> <li>c Connect DVM input to +28 VDC test jack</li> <li>d. Slowly increase dual dc power supply B output until DVM indication stops rising or drops suddenly</li> </ul>	
		e. DVM indicates +33.75 (±1.25) V at point of change	
27	Positive voltage crowbar check (+15 v)	a. Set dual dc power supply B output to 0 volts	If voltage level in f is out of tolerance, refer to paragraph
		<ul> <li>b. Set AUX AC switch to OFF then back to ON in e, refer to paragraph 4-7</li> <li>c. Connect dual dc power supply B (+) output to +15 VDC test</li> </ul>	4-39b. If voltage level can- not be adjusted or DVM indication is not as specified
		jack d. Connect DVM input to +15 VDC test jack	
		e. Slowly increase dual dc power supply B output until DVM indication stops rising or drops suddenly	
		f DVM indicates +18.75 (+1.25) V at point of change	
28	+5 V crowbar check	a. Set dual dc power supply B output to 0 volts	If voltage level in f is out of tolerance, refer to paragraph
		<ul> <li>b. Set AUX AC switch to</li> <li>OFF then back to ON</li> <li>paragraph 4-7</li> <li>c. Connect dual dc power</li> </ul>	4-39b. If voltage level cannot be adjusted or DVM indication is not as specified in e, refer to
		supply B (+) output to +5 VDC test jack	
		d. Connect DVM input to +5 VDC test jack	
		e. Slowly increase dual dc power supply B output until DVM indication stops rising or drops suddenly	
		f. DVM indicates +6.5 (-0.5) V at point of change	

equence no.	Item	Procedure	Reference
29	Positive voltage crowbar check (filtered +4.7 V)	Perform the following opera- tions: a. Set dual dc power supply	Paragraph 4-7
		<ul><li>B output to 0 volts</li><li>b. Set AUX AC switch to OFF then back to ON</li></ul>	
		c. Connect dual dc power supply B (+) output to FILTERED 4.7 VDC test jack	
		d. Connect DVM input to FILTERED 4.7 VDC test jack	
		e. Slowly increase dual dc power supply B output until DVM indication stops rising or drops suddenly	
		f DVM indicates +5.6 (+o.6) V at point of change	
30	Negative voltage crowbar check (-15 V)	a. Set dual dc power supply B output to 0 volts	If voltage level in f is out of tolerance, refer to paragraph 4-39b. If voltage level cannot
		<ul> <li>b. Set AUX AC switch to OFF then back to ON to paragraph 4-7</li> <li>c. Connect dual dc power supply B (-) output to -15 VDC test jack and B (+) output to EXT 28V RTN input jack</li> </ul>	be adjusted or DVM indication is not as specified in e, refer
		d. Connect DVM input to -15 VDC test jack	
		e. Slowly increase dual dc power supply B output until DVM indication stops rising or drops suddenly	
		f DVM indicates -18.75 (±1.25) V at point of change	
31	Negative voltage crowbar check (-25 V)	a. Set dual dc power supply B output to 0 volts	If voltage level in f is out of tolerance, refer to paragraph 4-39b. If voltage cannot be
		<ul> <li>b. Set AUX AC switch to OFF then back to ON to paragraph 4-7</li> <li>c. Connect dual dc power supply B (-) output to -25 VDC test jack</li> </ul>	adjusted or DVM indication is not as specified in e, refer
		d. Connect DVM input to -25 VDC test jack	

Sequence no.	ltem	Procedure	Reference
32	Shutdown	<ul> <li>e. Slowly increase dual dc power supply B output until DVM indication stops rising or drops suddenly</li> <li>f DVM indicates -30 (+i) V at point of change</li> <li>a. Set dual dc power supply B output to 0 volts</li> <li>b. Simultaneously set AC POWER and AUX AC switches to OFF</li> <li>c. Set 115 VAC switch to OFF</li> <li>d. Disconnect power supply 2AIPS1 from test fixture</li> <li>e. Connect wires removed in sequence no. 25, step e</li> </ul>	None

# 4-6. Special Purpose Electrical Cable Assembly Checks and Troubleshooting (fig. 5-9)

Checks and troubleshooting of special purpose electrical cable assemblies consists of a visual inspection of connectors, contacts (pins and sockets), and exterior tubing and continuity checks. Additional troubleshooting may be performed by resistance and hi-pot checks from pin to pin and pin to connector shell. Procedures for removal and replacement of connectors and connector contacts are contained in paragraph 3-47. A typical configuration of special purpose electrical cable assemblies is illustrated in figure 3-5.

# 4-7. Power Supply 2A1PS1 Troubleshooting Chart

The following chart provides procedures for isolating malfunctions to discrete components and modules. The numbers listed in the Sequence no. column correspond to the sequence numbers in the test procedure chart in paragraph 4-5c. The Symptom column lists the abnormal indications which may occur for the test with the corresponding sequence number. The Probable trouble column lists the discrete component(s) or module(s) most likely to cause the abnormal indication. The Corrective action column contains references to recommended procedures for correcting the trouble. When using standard fault isolation procedures, refer to figures 5-5 and 5-10 and the wire lists in appendix C, volume 2.

a. Troubleshooting Chart

Sequence no.		ltem	Procedure		Reference
1	a.	All of the following indica- tors light: (1) PS FAULT	a. A2 or KT	a.	Replace A2 (paragraph 4-12) or KI (paragraph 4-19)

equence no.	ltem	Procedure	Reference
		(2) VM NO GO (3) +VCB (4) -VCB (5) +5 VDC CB	
	b. Any of the following indi- cators light:	b Probable troubles are as follows:	b. Perform the following cor- rective action:
	(1) PS Fault	(1) A2	(1) Replace A2 (paragraph 4-1 2)
	(2) VM NO-GO	(2) A5	(2) Replace A5 (paragraph 412)
	(3) +VCB	(3) A4	(3) Replace A4 (paragraph 4-12)
	(4) -VCB	(4) A3	(4) Replace A3 (paragraph 4-12)
	(5) +5 VDC CB	(5) A7 or Q1	(5) Replace A7 (paragraph 4-11) or Q1 (paragraph 4-10)
	c. Any of the following com- binations of indicators ligh	c Probable troubles are as follows:	c Perform the following cor- rective action:
	(I) PS FAULT and VM	(1) VR2, VR3, VR4,	(1) Perform standard fault
	NO-GO VR6, VR7, or VR (2) PS FAULT and +VCB	8 (2) VR4, VR6, or VR8	isolation procedures (2) Perform standard fault isolation procedures
	(3) PS FAULT and -VCB	(3) V2 or VR3	(3) Perform standard fault isolation procedures
	(4) PS FAULT and +5 VDC CB	(4) VR7	(4) Replace VR7 (paragraph 4-29)
	d. DVNI indications not as d specified	A2 d, Replace A2 (paragraph 4-12)	
2	a. DVM indication not as specified	a. C4 through C9, R1, R2 R3, CR1, CR2, FLI, VRI, or T1	a. Perform standard fault isola- tion procedures
	b. Ripple level excessive	b. VR1	b. Replace VR1 (paragraph 4-15)
3	a. DVM indication not as specified	a. FL2	a. Perform standard fault isolation procedures
	b. Ripple level excessive	b. C6, C7, or CS	b Perform standard fault isolation procedures
5	a. DVM indication not as specified	<ul> <li>A5, A4, FL7, VR4, RI1, R9,</li> <li>A6R7, A6R5, K2, A6CR6, tion procedures</li> <li>C12, L2, A1Z1, A1Z2, A1T1,</li> <li>K1, C1 through C4. or A2</li> </ul>	a. Perform standard fault isola-
	b. Ripple level excessive	b. VR4	b. Replace CR4 (paragraph 4-16)
		4-12	

Sequence no.	ltem	Procedure	Reference
6	a. DVM indication not as specified	a. A5, A4, VR6, FL9, R20, R21, or A6CR11	a. Perform standard fault isola- tion procedures
	b. Ripple level excessive	b. VR6	b. Replace VR6 (paragraph 4-17)
7	a. DVM indication not as specified	a. A5, A7, Q1 R22, C15, FLS, FL10, FL11, A6R12, A6CR7, C13, L3, A1Z3, A1Z4, ATTI, VR7A6, VR7L1, VR7R3 through VR7R4, VR7C1, VR7C2, VR7C3, VR7Q1, VR7Q2, or VR7CR1	a. Perform standard fault isolation procedures
	b. Ripple level excessive	b. VR7A1	b. Replace VR7A1 (paragraph 4-33)
8	a. DVM indication not as specified	a. A5, A4, VR8, R15, R16, R19, A6CR10, C14, FL12, or CR12	a. Perform standard fault isola- tion procedures
	b. Ripple level excessive	b. VR8	b. Replace VR8 (paragraph 4-15)
9	a. DVM indication not as specified	a. A1Z1 A122, L1, C11, A6R6, FL6, R2, A6R4, A6CR8, R13, R17, A5, A3, or VR3	a. Perform standard fault isola- tion procedures
	b. Ripple level excessive	b. VR3	b. Replace VR3 (paragraph 4-16)
10	a. DVM indication not as specified	a. A6CR5, R8, R10, FL5, A3, A5, or VR2	a. Perform standard fault isola- tion procedures
	b. Ripple level excessive	b. VR2	b. Replace VR2 (paragraph 4-16)
12	DVM indication not as specified and/or ripple level excessive	VR4	Replace VR1 (paragraph 4-16)
13	DVM indication not as specified and/or ripple level excessive	VR6	Replace VR6 (paragraph 4-16)
14	DVM indication not as specified and/or ripple level excessive	VR7A1, VR7Q1, or VR7Q2	Perform standard fault isolation procedures
15	a. DVM indication not as specified	a CR12 or VR8	a. Perform standard fault isola- tion procedures
	b Ripple level excessive	b. VRS	b. Replace VR8 (paragraph
16	DVM indication not as specified and/or ripple level excessiv		4-15) Replace VR3 (paragraph 4-16)
17	DVM indication not as specified	VR2	Replace VR2 (paragraph 4-16)

Sequence no.	Item	Procedure	Reference
19	PS FAULT and VM NO-GO indicators do not light aid/or DVM indications 01ot as specified	A2, A4, or A5	Perform standard fault isolation procedures
20	PS FAULT and VMI NO-GO indicators do not go out	A2	Replace A2 (paragraph 4-12)
21	PS FAULT and V NO-GO indicators do not light and/or DVM indications not as specified	A3 or A5	Perform standard fault isolation procedures
23	PS FAULT indicator does not go out	A2	Replace A2 (paragraph A-12)
24	PS FAULT indicator does not light	A2	Replace A2 (paragraph 4-12)
26	DVM indication not as specified	A4 or A2	Perform standard fault isolation procedures
27	DVM indication not as specified	A4	Replace A4 (paragraph 4-12)
28	DVM indication not as specified	A7 or A2	Perform standard fault isolation procedure
29	DVM indication not as specified	A4	Replace A4 (paragraph 4-12)
30	DVM indication not as specified	A3 or A2	Perform standard fault isolation procedures
31	DVM indication not as specified	A3	Replace A3 (paragraph 4-1 2)

# Section III. REMOVAL, REPLACEMENT, REPAIR, AND ADJUSTMENTS

#### 4-8. General

Procedures in this section provide instructions for removal and replacement of components, assemblies, and modules of power supply 2AIPS1 and repair of special purpose electrical cable assemblies.

# NOTE

When performing replacement procedures, use sealant on attaching hardware when a mechanical locking

device (lockwasher, locknut, etc) is not specified.

# 4-9. Instructions for Removal and Replacement of Power Supply 2AIPSI Modules, Assemblies, and Components

Procedures in paragraphs 4-10 through 4-38 apply to modules, assemblies, and components of power supply PSI. Refer to figure 5-10for location of components not indexed in figure 4-2. Upon completion of removal and replacement procedures in paragraph 4-10 through 4-38, perform test procedures in paragraph 4-5.

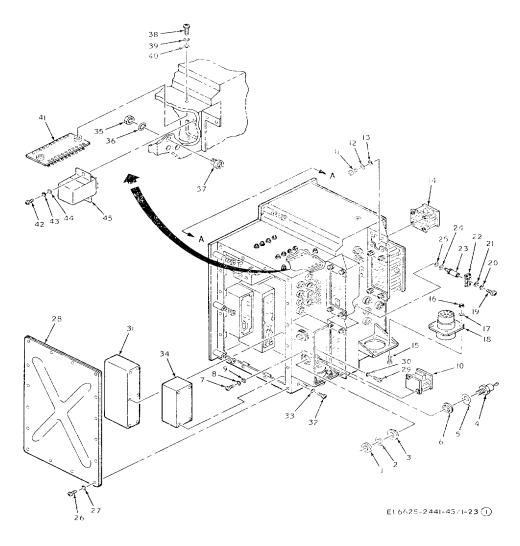
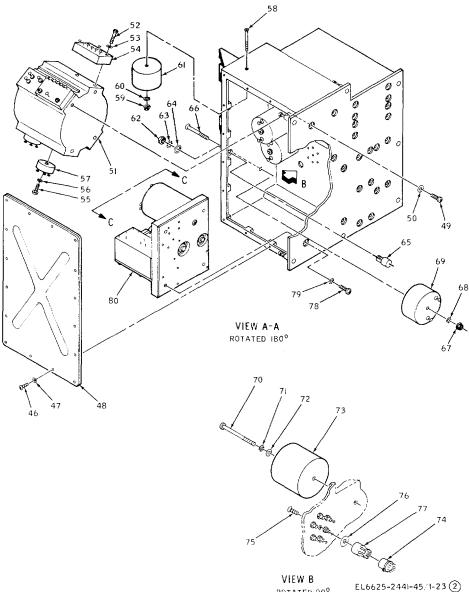


Figure 4-2 (1). Power Supply 2A IPSI, exploded view (part 1 of 3)

- 1 Nut (2)
- 2 Flatwasher (2)
- 3 Insulating shoulder washer (2)
- 4 Semiconductor (2; 2AIPSIQ1, 2A1PSICR12)
- 5 Lug (2)
- 6 Insulating shoulder washer (2)
- 7 Screw (2)
- 8 Locekwasher (2)
- 9 Flatwasher (2)
- 10 +5 V crowbar 2AIPSIA7
- 11 Screw (16)
- 12 Lockwasher (16)
- 13 Flatwasher (16)
- 14 Module (4: 2ÁIPSIA2, 2AIPSIA3, 2A1PS1A4, 2AIPSIA5)
- 15 Screw (8)
- 16 Locknut (8)
- 17 Flatwasher (8 i0 Flat40.hcr 1'9
- 18 Connector (2; 2AIPSIJI, 2AIPSIJ2)
- 19 Screw
- 20 Lockwasher 21 Flatwasher
- 22 Bus bar 2AIPSIW1
- 23 Insulated standoff

- 24 Lockwasher 25 Flatwasher
- 26 Screw (14)
- 27 Flatwasher (11t)
- 28 Covet-
- 29 Screw (12)
- 30 Flatwashec (12)
- 31 Voltage regulator (2; 2A1 PS1 VR,R 2A1PS1VR8)
- 32 Screw (16)
- 33 Flatwasher (16)
- 34 Voltage regulator (4; 2AIPSIVR2, 2AIPS1VR3, 2AIPS1 VR4, 2AIPS1VR6)
- 35 Nut (12)
- 36 Lockwasher (12)
- 37 Filter (12, 2APSIFLI through 2AIPSIFL12)
- 38 Screw (2)
- 39 Lockwasher (2)
- 41 Component assembly 2A1PS1A6
- 42 Screw (3)
- 43 Lockwasher (3)
- 44 Flatwasher (3)
- 45 Relay 2A1IPS1K1



ROTATED 90°

Figure 4-2 (2). Power Supply 2A1PS1, exploded view (part 2 of 3).

46 Screw (14) 47 Flatwasher (14) 48 Cover 49 Screw (4) 50 Flatwasher (4) 51 Transformer rectifier assembly 2AIPSIA1 52 Screw (4) 53 Flatwasher (4) 54 Diode assembly (2; 2AIPSIAIZ3, 2AIPSIAIZ4) 55 Screw (2) 56 Flatwasher (2) 57 Diode assembly (2; 2AIPSIAIZ1, 2AIPSIAIZ2) 58 Screw 59 Locknut 60 Flatwasher 61 Transformer 2ATPSIT1 62 Nut (5) 63 Lockwasher (5) 2AIPSIVR7

- 64 Flatwasher (5)
- 65 Capacitor (5, 2AIPSICI through 2AIPSIC5)
- 66 Screw
- 67 Locknut
- 68 Flatwasher
- 69 Inductor 2AIPSIL3
- 70 Screw (2)
- 71 Lockwasher (2)
- 72 Flatwasher (2) 73 Inductor (2; 2AIPSILT, 2AIPSIL2) 74 Relay 2AIPS1K2
- 75 Screw
- 76 Flatwasher 77 Heat sink 2AIPSIMP4
- 78 Screw (5) 79 Flatwasher (5)
- 80 +5 V switching regulator

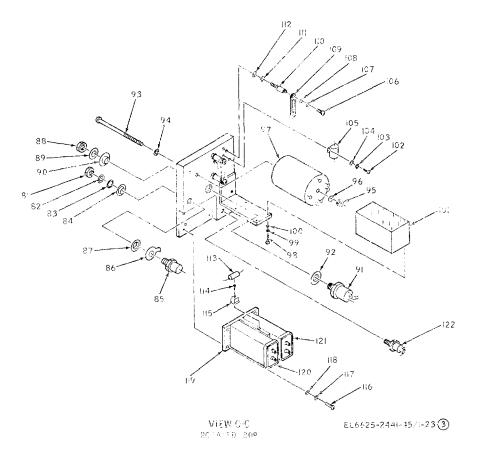


Figure 4-2 (3). Power Supply 2A1PS1, exploded view (part 2 of 3).

81 Nut 82 Lockwasher

- 83 Flatwasher
- 84 Insulating shoulder washer
- 85 Diode 2AIPSIVR7CRI
- 86 Lug
- 87 Insulating shoulder washer
- 88 Nut
- 89 Flatwasher
- 90 Insulating shoulder washer
- 91 Transistor 2A1PS1VR7Q2 92 Insulating shoulder washer
- 93 Screw
- 94 Flatwasher
- 95 Locknut
- 96 Flatwasher
- 97 Inductor 2AIPS1VR7LI
- 98 Screw (4)
- 99 Lockwasher (1)
- 100 Flatwasher (4)
- 101 Regulator controller assembly 2A1PS1VR7A1 2A1PS1VR7Q1
- 4-10. Removal and Replacement Semi-conductors 2A1PS1CR12 and 2A1PS1Q1 (fig. 4-9,)
  - a. Removal

## NOTE

When removing semiconductor 2A1PS1Q1, do not remove resistor 2A1PS1R22 or

- 102 Screw (4)
- Lockwasher (4) 103
- 104 Flatwasher (4)
- 105 Resistor (2; 2A1PS1VR73, 2A1PS1VPSR4)
- Screw (4) 106
- 107 Lockwasher (4)
- Flatwasher (4) 108
- 109 Bus bar (2: 2A1PS1VR7W1, 2A1PS1VPSR7W2)
- Insulated standoff (4i 110
- 111 Lockwasher (4)
- Flatwasher (1) 112
- 113 Capacitor 2A1PS1VR7C3,
- 114 Screw
- 115 Clip
- Screw (4) 116
- 117 Lockwasher(4) Flatwasher (1)
- 118 119
- Capacitor bracket Capacitor 2A1PS1VR7C1 120
- 121 Capacitor 2A1PS1VR7C2
- 122 Transistor

capacitor 2A1PS1R15 from 2A1PS1Q1 terminals.

(1) Tag and unsolder wires from semi conductor and lug.

(2) Remove nut (1), flatwasher (2), insulating shoulder washer (3), semiconductor (4), lug (5) and insulating shoulder washer (6)

b. Replacement

## NOTES

 Before insulating semiconductor 2A1PS1Q1, attach replacement resistor 2A1PS1R22 and capacitor 2A1PS1C15 to transistor terminals.
 Apply a thin coating of insulating compound to insulating shoulder washer (3) and (6) before installing

(1) Attach semiconductor (4) to mounting bracket using lug (5), insulating shoulder washer (6) and (3) flatwasher (2), and nut 1)

(2) Solder tagged wires to proper semiconductor terminals and lug.

# 4-11. Removal and Replacement of +5V Crowbar 2A1PS1A7

a. Removal

(1) Tag and remove wires from terminals of +5 V crowbar A7  $\,$ 

(2) Remove two screws (7), lockwashers (8), and flatwashers (9); remove +5 V crowbar A7 (10)

## b. Replacement

(1) Attach +5 V crowbar A7 (10) to bracket using two flatwashers (9), lockwashers (8, and screws (7)

(2) Solder tagged wires to proper terminals of +5 V crowbar A7.

# 4-12. Removal and Replacement of Modules 2A1PS1A2 through 2A1PS1A5

a. Removal

(1) Tag and unsolder wires from assembly terminals.

(2) Remove four screws (11), Lockwashers(12) and flatwashers (13); remove assembly (14)

b. Replacement

(1) Attach assembly (14) to bracket using four flatwashers (13) Lockwashers and screws (11).

(2) Solder tagged wires to proper assembly terminals.

# 4-13. Removal and Replacement for Connectors 2A1PS1J1 and 2A1PS1J2.

a. Removal

(1) Tag and remove wires and contacts from connector.

(2) Remove four screws (15), locknut s (16), and flatwashers (17); remove connector (18)

b. Replacement

(1) Attach connector (18) to bracket using four flatwashers (17), locknuts (16), and screws (15)

(2) Insert tagged wires and contacts into connector.

# 4-14. Removal and Replacement of Bus Bar 2A1PS1W1

- a. Removal
  - (1) Unsolder wires from bus bar W1.

(2) Remove scr4ew (19), lockwasher (20), and flatwasher (21); remove bus bar W1 (22). If insulated standoff; remove lockwasher (24) and flatwasher (25)

b. Replacement

(1) If insulated standoff (23) has been removed, attach insulated standoff, flatwasher (25), and lockwasher (24) to power supply chassis. Attach bus bar W1 (22) to insulated standoff (23) using flatwasher (21), lockwasher (20), and screw (19)

4-18

(2) Solder wires to bus bar W1

## 4-15. Removal and Replacement of Voltage Regulators 2A1PS1VRA1 and 2A1PS1VR8 (fig 4-2)

#### a. Removal

(1) Remove 14v screws (26) and flatwashers (27); remove cover (28).

(2) Tag and unsolder wires from terminals of voltage regulator

(3) Remove six screws (29), and flatwashers, (30), remove voltage. Regulator (31) with discrete components (s) attached..

#### b. Replacement

### NOTE

Before installing replacement voltage regulator, mount discrete components on voltage regulator. Refer to figures 5-5 and 5-10 for reference designations and location

(1) .attach voltage regulator (31); to power supply chassis using six flatwashers (30) and screws (29-).

(2) Solder tagged wires to voltage regulator terminals.

(3) attach cover (28) using 14 flatwashers (27) and screws (26). Do not use two corner holes adjacent to power supply -mounting plate.

## 4-16. Removal and Replacement of Voltage Regulators 2A1PS1VR2, 2A1PS1VR3, 2A1PS1VR4, AND 2A1-S1VR6

### a. Removal

(1) Remove 14 screws (26) and flatwashers (27); remove cover (28).

(2) Tag and unsolder wires from voltage regulator terminals

(3) Remove four screws (32) and flatwasher (38); remove voltage regulator (34) with discrete components (s) attached

b. Replacement

#### NOTE

Before installing voltage regulator, mount discrete components on replacement voltage regulator. Refer to figure 5-5b and 5-10 for reference designations locations.

(1) Attach voltage regulator (34) to power supply chassis using four flatwashers (33) and screws (32)

(2) Solder tagged wires to voltage regulator terminals.

(3) Attach cover (28) using 14 flatwashers (27) and screws (26). Do not use corner holes adjacent to power supply mounting plate.

### 4-17. Removal and Replacement of Filters 2A1PS1FL1 through 2A1PS1FL12 (fig 4-2)

When performing removal and replacement procedures for filters FL1, FL2, FL4 through FL7, FL9, or FL12, remove and replace cover (28). For filters FL3, FL8, FL10, or FL11, remove and replace cover (48)

a. Removal

(1) Remove 14 screws (26) or (46) and flatwashers (27) or (47); remove cover (28) or (48)

(2) Unsolder wires from filter terminals

(3) Remove nut (35) using Lockwasher (36) and nut (35)

b. Replacement

(1) Attach filter 37) using lockwasher (36) and

nut (35)

(2) Solder wires to filer terminals

4-19

(3) Attach cover (28) or (48) using 14 Flatwashers (27) or (47) and screws (26) or (46). Do not use two corner holes adjacent to power supply mounting plate.

## 4-18. Removal and Replacement of Component Assembly 2A1PS1A6 (fig. 4-2)

a. Removal

(1) Remove 14 screws (26) and flatwashers (27); remove cover (28).

(2) Tag and unsolder wires from component assembly A6 terminals.

(3) Remove two screws (38), lockwashers (39), and flatwashers (40); remove component assembly A6 (41).

b. Replacement

(1) Attach component assembly A6 (41) to power supply chassis using two flatwashers (40), lockwashers (39), and screws (38).

(2) Solder tagged wires to component assembly A6 terminals.

(3) Attach cover (28) using 14 flatwashers (27) and screws (26). Do not use two corner holes adjacent to power supply mounting plate.

# 4-19. Removal and Replacement of Relay 2A1PS1K1 (fig. 4--2)

a. Removal

(1) Remove 14 screws (46) and flat washers (47): remove cover (48).

(2) Tag and unsolder wires from relay terminals.

(3) Remove 14 screws (26,) flatwashers, (27); remove cover (28).

(4) Remove three screws (42), lockwashers (43), and flatwashers (44); remove relay K1 (45).

b. Replacement

### NOTE

Before installing relay K1, attach diode 2A1PS1CR3 to pin X1 and X2 of relay K11. Refer to figure 5-10 for polarity.

(1) Attach relay K 1 (45) to power supply chassis using three flatwashers (44), lockwashers (43), and screws (42)

(2) Solder tagged wires to relay K1 terminals.

(3) Attach cover (48) using 14 flatwashers (47) and screws (46).

(4) Attach cover (28) using 14 flatwashers (27) and screws (26). Do not use two corner holes adjacent to power supply mounting plate.

## 4-20. Removal and Replacement of Transformer Rectifier Assembly 2A1PS1A1 (fig. 4-2)

a. Removal

(1) Remove 14 screws (46) and flatwashers (47); remove cover (48).

(2) Remove four screws (49) and flatwashers(50). Carefully remove transformer rectifier assemblyA1 (51) from power supply chassis.

(3) Tag and unsolder all input and output leads from transformer rectifier assembly A1 terminals.

b. Replacement

(1) Solder tagged wired to transformer rectifier assembly A1 terminals

### CAUTION

Insure that wiring is clean when installing transformer rectifier assembly A1 in power supply chassis.

(2) Attach transformer rectifier assembly A1 (51) to power supply chassis using four flatwashers (50

(3) Attach cover (48) using 14 flatwashers (47) and screws (46). Do not use two comer holes adjacent to power supply mounting plate.

## 4-21. Removal and Replacement of Diode Assemblies 2A1PS1A1Z3 and 2AIPSIAIZ4 (fig. 4-2)

a. Removal

(1) Remove cover and transformer rectifier assembly as described in 4-20a(1) and (2).

(2) Tag and unsolder wires from diode assembly terminals.

(3) Remove two screws (52) and flatwashers (53); remove diode assembly (54) from transformer rectifier assembly 2A1PS1A1 (51).

b. Replacement

(1) Attach diode assembly (54) to transformer rectifier assembly 2A1PS1A1 (5i) using two flatwashers (53) and screws (52).

(2) Solder tagged wires to diode assembly terminals.

(3) Install transformer rectifier assembly 2AIPS1AI and cover as described in 4-20b(2) and (3).

# 4-22. Removal and Replacement of Diode Assemblies 2AIPSIA1Z1 and2AIPSIAIZ2 (fig. 4-2)

a. Removal

(1) Remove cover and transformer rectifier assembly as described in 4-20a(1) and (2).

(2) Tag and unsolder wires from diode assembly terminals.

(3) Remove screw (55) and flatwasher (56); remove diode assembly (57) from transformer rectifier assembly 2AIPS1A1 (51).

b. Replacement

(1) Attach diode assembly (57) to transformer rectifier assembly 2A1PSIA1 (51) using flatwasher (56) and screw (55).

(2) Solder tagged wires to diode assembly terminals.

(3) Install transformer rectifier assembly 2AIPSIA1 and cover as described in 4-20b(2) and (3).

# 4-23. Removal and Replacement of Transformer 2AIPSITI (fig. 4-2)

a. Removal

(1) Remove 14 screws (46) and flatwashers (47); remove cover (48).

(2) Tag and unsolder wires from transformer TI terminals.

(3) Remove screw (58), locknut (59), and flatwasher (60): . remove transformer T1 (61).

b. Replacement

(1) Attach transformer T1 (61) to power supply chassis using flatwasher (60), locknut (59), and screw (58).

(2) Solder tagged wires to transformer T1 terminals, (3) Attach cover (48) using 14 flatwashers (47) and screws (46).

# 4-24. Removal and Replacement of Capacitors 2AIPSICI through 2A1PS1C5 (fig. 4-2)

a. Removal

(1) Remove 14 screws (46) and flatwashers (47); remove cover (48).

(2) Tag and unsolder wires from capacitor terminals.

(3) Remove nut (62), lockwasher (63), and (flatwasher (64), remove capacitor (65).

4-21

b. Replacement

(1) Attach capacitor (65) to power supply chassis using flatwasher (64), lockwasher (63), and nut (62)

(2) Solder tagged wires to capacitor terminals.

(3) Attach cover (48) using 14 flatwashers (47) and screws (46). Do not use two corner holes adjacent to power supply mounting plate.

# 4-25. Removal and Replacement of Inductor 2A1PS1L3 (fig 4-2)

a. Removal.

(1) Remove 14 screws (46) and flatwasher (47); remove4 cover (48).

(2) Tag and unsolder wires from inductor L3 terminals.

(3) Remove screw (66) locknut (67) and flatwashers (68); remove inductor L3 (69

## b. Replacement

(1) Attach inductor (73) to power supply chassis using flatwasher (72), lockwasher (71), and screw (70).

(2) Solder tagged a. wires to inductor L3 terminals..

(3) Attach cover (48) using 14 flatwashers (47) and screws (47). Do not use two corner holes adjacent to power supply mounting plate.

# 4-27. Removal and Replacement of Relay 2A1PS1K2 (fig. 4-2)

a. Removal

(1) Remove 14 screws (26) and flatwashers (27); remove cover (28).

(2) Unsolder relay K2 leads from terminals 2A1PS1E4 through 2A1PS1E9.

(3) Note position of relay index tab, and carefully pull relay K2 (74) from heat sink 2A1PS1MP4.

b. Replacement

(1) Carefully insert relay K2 (74) into beat sink 2A1PS1MP4 (77). Insure that index that is in same position as noted in removal of tab.

(2) Solder leads of relay K2 to proper terminals (refer to figure 5-5 for connections).

(3) Attach cover (28) using 14 flatwashers (27) and screws (26). Do not use holes adjacent to power supply mounting plate.

# 4-28. Removal and Replacement of Heat Sink 2A1FSIAP4 (fig. 4-2.

a. Removal.

(1) Remove K2 as described in 4-276a.

4-22

(2) Remove 14 screws (46) and flatwashers (47); remove cover (48),

(3) Remove screw (75)) and flatwasher (76); remove cover heat sink MP4 (77)

b. Replacement

(1,) Attach heat sink MP4 (77) to power supply chassis using flatwasher (76) and screw (75).

(2) Attach cover (48) using 14 flatwashers (47) and screws (46).

(3) Install relay 2AiPS1K2 and cover as described in 4—27b.

## 4-29. Removal and Replacement of +5V Switching Regulator 2A1PS1VR7 (fig. 4--2)

a. Removal

(1) Remove 14 screws (46) and flatwashers (47); remove cover (48).

(2) Tag and unsolder all input and output wires from +5 V switching regulator VR7 terminals.

(3) Remove five screws (78) and flatwashers ('47); remove +5 V switching regulator VR7 (80)

b. Replacement

(1) Attach +5 V switching regulator VR7 (80) to power supply chassis using five flatwashers (79) and screws (78).

(2) Solder tagged wires to 45 V s regulator VR7 terminals.

(3) Attach cover (48) using 14 flatwashers (47) and screws (46). Do not use two corner holes adjacent to power supply mounting plate.

## 4-30. Removal and Replacement of Diode 2A1PS1VR7CR1 (fig. 4-2)

a. Removal

(1) Remove +5 V switching regulator 2A1PS1VR7 as described in 4-29a.

(2) Tag and unsolder wires from diode CR1 and lug.

(3) Remove nut (81), lockwasher (82), flatwasher (83), and insulating shoulder (84); remove diode CR1 (85). lug (86), and insulating shoulder washer (87).

b. Replacement

### NOTE

Before installing diode CR1. apply thin coating of insulating compound to insulating shoulder washers (84) and (87).

(1) Attach insulating shoulder washer (87), lug (86) and diode CR1 (85) to base using insulating shoulder washer (83), lockwasher (82), and nut (81)

(2) Solder tagged wires to lug and diode CR1.

(3) Install +5 V switching regulator 2A1PS1VR7 in power supply chassis 3s described in 4-29b.

## 4-31. Removal and Replacement of Transistor 2A1PS1VR7Q2 (fig. 4-2)

a. Removal

(1) Remove +5 V switching regulator 2A1PS1VR7 as described in 4-29a.

(2) Tag and unsolder wires from transistor Q2 terminals.

(3) Remove nut (88), flatwasher (89) and insulating shoulder washer (90); 1.remove transistor Q2 (91), with resistor 2A1PS1VR7R2 attached, and insulating shoulder washer ('92).

b. Replacement

### NOTE

Before installing transistor Q2, apply a thin coat of insulating compound to insulating sho9ulder washers (90) and (92)

(1) Attach insulating shoulder washer (892) and transistor Q2 (91) to mounting shoulder washer (90), flatwasher (89), and nut (88).

(2) Solder tagged wires and replacement resistor 2A1PS1VR7R2 to proper transistor Q2 terminals.

(3) Installed +5 V switching regulator 2A1PS1VR7 as described in 4-29b.

# 4-32. Removal and Replacement of Inductor 2A1PS1VR7L1 (fig 4-2)

a. Removal.

(1) Remove +5 V switching regulator 2A1PS1VR7 as described in 4-29a.

(2) Tag and unsolder wires from regulator controller assembly A1 terminals.

(3) Remove screws (93), lockwashers (94), Locknut, flatwashers (96); remove regulator inductor L1 (97).

b. Replacement

(1) Attach inductor L1 (97) using flatwasher (96), locknut (95), flatwasher (94) and screw (93).

(2) Solder tagged wires to inductor L1 terminals.

(3) Install +5 V switching regulator 2A1PS1VR7 as described in 4-29b.

## 4-33. Removal and Replacement of Regulator Controller Assembly 2A1PS1VR7A1 (fig 2)

a. Removal

(1) Remove +5 V switching regulator 2A1PS1VR7 as described in 4-29a.

(2) Tag and unsolder wires from regulator controller assembly terminals.

b. Replacement

(1) Attach regulator controller assembly A1(101) to the mounting bracket using four flatwashers(100), lockwashers (99), and screws (98).

(2) Solder tagged wires to regulator controller assembly A1 terminals.

(3) Install +5 V switching regulator 2A1PS1VR7 as described in 4-29h.

## 4-34. Removal and Replacement of Resistors 2A1PS1VR7R3 and 2A1PS1VR7R4 (fig. 4-2)

a. Removal

(1) Remove +5 V switching regulator 2A1PS1VR7 as described in 4-29a.

(2) Unsolder wires from resistor terminals.

(3) Remove two screws (102), lockwashers (103), and flatwashers (104); remove resistor (105).

b. Replacement

(1) Attach resistor (105) to mounting base using two flatwashers (104), lockwashers (103), and screws (102).

(2) Solder wires to resistor terminals.

(3) Install +5 V switching regulator 2A1PS1VR7 as describe in 4-295b.

## 4-35. Removal and Replacement of Bus Bars 2A1PS1VR7WI and 2A1PS1VR7W2 and Insulated Standoffs (fig. 4-2)

The following removal and replacement procedures include removal and replacement of

4-24

the insulated standoffs. Remove and replace bus bar or insulated standoff as required.

a. Removal

(1) Remove +5 V switching regulator 2AIPSIVR7 as described in 4-29a.

(2) Unsolder wires from bus bar only if bus bar is to be replaced.

(3) Remove two screws (106), lockwashers (107), and flatwashers (108); remove bus bar (109).

(4) Remove two insulated standoffs (110), lockwashers (111), and flatwashers (112).

b. Replacement

(1) Attach two flatwashers (112), lockwashers (111), and insulated standoff (110) to mounting base.

(2) Attach bus bar (109) to insulated standoffs (110) using two flatwashers (108), lockwashers (107), and screws (106).

(3) Solder wires to bus bar if bus bar was replaced.

(4) Install +5 V switching regulator 2AIPSIVR7 as described in 4-29b.

# 4-36. Removal and Replacement of Capacitor 2A1PS1VR7C3 and Clip (fig. 4-2)

a. Removal

(1) Remove +5 V switching regulator 2AIPSIVR7 as described in 4-29a.

(2) Unsolder capacitor C3 leads from diode 2A1PS1VR7CR1 and transistor 2AIPSIVR7Q2. Remove capacitorC3 (113) from clip (115).

(3) Remove screw (114) and clip (115) from capacitor bracket (119).

b. Replacement

(1) Attach clip (115) to capacitor bracket (119) using screw (114).

(2) Place capacitor C3 (113) in clip (115). Solder capacitor C3 leads to diode 2A1PS1VR7CR1 and transistor 2A1PS1VR7Q2.

(3) Install +5 V switching regulator 2A1PS1VR7 as described in 4-29b.

# 4-37. Removal and Replacement of Capacitors 2A1PS1VR7C1 and 2AIPSIVR7C2 (fig. 4-2)

The following removal and replacement procedures provide the necessary instructions for replacing capacitors C1 and C2. The capacitors are bonded to the capacitor bracket with epoxy adhesive.

a. Removal

(1) Remove +5 V switching regulator 2A1PSIVR7 as described in 4-29a.

(2) Remove capacitor 2A1PSIVR7C3 (113) from clip (115). Do not unsolder capacitor C3 leads.

(3) Tag and unsolder wires from capacitor C1 and C2 terminals.

(4) Remove four screws (116), lockwashers (117), and flatwashers (118); remove capacitor bracket (119) with capacitors C1 (120) and C2 (121) attached.

(5) Remove faulty capacitor from capacitor bracket and clean all epoxy adhesive residue from capacitor bracket.

b. Replacement

(1) Apply thin film of epoxy adhesive to bonding surfaces of replacement capacitor and capacitor bracket. Press surfaces together firmly.

(2) Cure epoxy adhesive in precision oven for 2 hours minimum at  $165^{\circ}$  (+5°)F or 7 days at room temperature of 750 (+-5°)F.

4-25

(3) Attach capacitor bracket (119) to mounting base using four flatwashers (118), lockwashers (117) and screws (116).

(4) Solder tagged wires to terminals of capacitors C1 (120) and C2 (121).

(5) Insert capacitor 2A1PS1VR7C3 into clip (115).

(6) Install +5 V switching regulator 2A1PS1VR7 as; described in; 4-29b.

# 4-38. Removal and Replacement of Transistor 2A1PS1VR7Q1 (fig. 4--2)

## a. Removal

(1) Remove -+-5 V Switching regulator 2A1PS1VR7 as described in 4-29a.

(2) Tag and unsolder wires from transistor terminals.

(3) Remove transistor Q1 (122) with resistor 2A1PS1VR7R1 attached.

b. Replacement

(1) Screw transistor Q1 (122) into mounting base.

(2) Solder resistor 2A1PS1VR7R1 and tagged wires to proper transistor Q1 terminals.

(3) Install +5 V switching regulator 2A1PSVIR7 as described in 4-29b.

# 4-39. Special Purpose Electrical Cable Assembly Repair

Repair of special purpose electrical cable assemblies is limited to replacement of connectors or connector contracts. A typical -configuration of single and multiconductor shielded cable is illustrated in figure 3-5. Refer to figure 5-9 for special purpose electrical cable assembly wiring. Paragraph 3-47 lists the cable contact tools. Proceed as. described in paragraph 3--47a and, use standard maintenance practices when replacing, connector contacts..

### WARNING

4-26

Power supply 2A1PS1 contains voltages which may cause DEATH or SERIOUS INJURY. Be careful when making adjustments.

## CAUTION

Some of power supply 2A1PS1 adjustments are very close to exposed pins and terminals. Use extreme caution when making adjustments to prevent damage to power supply 2A1PS1.

# 4-40. Power Supply 2A1PS1 Adjustments (fig. 5 10)

Procedures contained in this paragraph provide instructions for adjusting power supply voltages .and crowbar thresholds. These adjustments are made in conjunction with test procedures and after replacement of modules.

a. Power Supply 2A1PS1 Voltage Adjustment Chart. The following chart lists the power supply voltage adjustments with the corresponding potentiometers. The numbers listed in the Sequence no. column correspond to the sequence numbers in the test procedure chart (paragraph 1-5c) for tests in which voltage adjustments are recommended. The Potentiometer column lists the reference designation of the potentiometer to be adjusted. The DVM indication column lists the voltage requirement of each adjustment. Refer to figure 5-0 for potentiometer locations.

Sequence no.	Potentiometer	D indic	VM ation	(V)	
2	VR1R13	+4.69	to	+4.71	
5	VR4R14	+27.94	to	+28.05	
6	VR6R14	+14.97	to	+15.03	
7	VR7AIR13	+4-99	to	+5.01	
8	VR8R13	+4 69	to	+4.71	
9	VR3R14	+14 97	to	-15.03	
10	VR2R14,	-24.95	to	-25.05	

b. Power Supply 2A1PS1 Crowbar Adjustment C1iart. The following chart lists the adjustments required to set each crowbar threshold to the proper level. The numbers listed in the Sequence no. column correspond to the sequence numbers in the test procedure chart (paragraph 4-5c) for tests in which crowbar adjustments are recommended. The Potentiometer column lists the reference designation of the potentiometer associated with each crowbar. The DVM indication column lists the acceptable voltage range of each adjustment. It may be necessary to repeat

Sequence no	D\ indica	/M ation (	(V)	
26	V4R14	+32.5	to	+35.0
27	V4R14	+17.5	to	+20.0
28	V7R7	+6.07	to	+7.0
30	V3R16	-17.5	to	-20.0
31	V3R16	-29.0	to	-31.0

# Section IV. DEPOT OVERHAULS STANDARDS

## 4-41. Applicability of Depot Overhaul Standards

The tests outlined in this section are designed to measure the performance capability of a repaired equipment. Equipment that is to be returned to stock should meet the standards given in these tests.

### 4-42. Applicable References

a. Repair Standards. Applicable procedures and the general standards for repaired electronic equipment are given in TB S1G 355-1, Depot Inspection Standard for Repaired Signal Equipment; TB S1G 355-2, Depot Inspection Standard for Refinishing Repaired Signal Equipment; and TB S1G 355-3, Depot Inspection Standard for Moisture and Fungus Resistant Treatment and TM, -6625?441-45-1 the procedures of the referenced sequence number to obtain the desired results. Refer to figure -5-10 for potentiometer locations. form a part of the requirements for testing the equipment.

b. Modification Work Orders. Perform all applicable modification work orders pertaining to this equipment before making the tests specified. DA Pam 310-7 lists all current MWO's.

## 4-43. Test Facilities Required

The test facilities required are identical to those specified in paragraph 4-2.

## 4-44. Test Procedures

Test procedures are the same as the confidence check and automatic self test procedures in TM 11-6625-2441-12. Acceptable standards of performance for depot overhaul are the same as those given in these tests.

# **APPENDIX A**

# REFERENCES

The following publications contain information applicable to the operation and maintenance of Test Set, Navigational Computer-Control Indicator AN/ASM-386.

DA Pam 310-4	Military Publications: Index of Technical Manuals, Technical Bulletins, Supply Manuals (types 7, 8, and 9), Supply Bulletins, and Lubrication Orders.
DA Pam 310-7	U.S. Army Equipment Index of Modification Work Orders.
TM 11-6625-2441-12	Operator's and Organizational Maintenance Manual: Test Set, Navigational Computer-Control Indicator AN/ASM-386.
TM 11-6625-2441-20P	Organizational Maintenance Repair Parts and Special Tools List: Test Set, Navigational Computer-Control Indicator AN/ASMA386.
TM 11-6625-2441-45P	General Support and Depot Maintenance Repair Parts and Special Tools List: Test Set, Navigational Computer-Control AN/ASM-386.

### Section I. INTRODUCTION

PROGRAM

## B-1. General

This appendix contains the self-test program listing in This section contains a list of column section II. headings used in the listing, with explanations of entries and definitions of abbreviations and symbols used.

## **B-2.** Program Listing Column Heading and Entries

Column headings and entry definitions are listed in a below. Abbreviations and symbol definitions are listed in b below.

- a. Column Heading Listing
- Column heading

Entry

- TEST NO. A four-digit, two-part test indication displayed on the LCU front panel TEST NUMBER indicator. The two most significant digits from 00 through 99 indicate the major test being performed. The two least significant digits from 00 through 99 indicate the minor test, the lower order of the major test being performed.
- **DEC1SION** Any digit from 1 through 12. A 1 LEVEL indicates that all previous tests have been successfully completed; i.e., this is the first decision level for each test. When applicable test conditions exist, a yes/no or go/no-go decision must be made. A 2 or subsequent number indicates the lower order test condition at which that decision is made.
- TEST/FAULT The entry in this column is an alpha numeric code indicating a test or a NUMBER fault location. test sequence number, and no-go flag state. A T denotes a test, and an F denotes a fault location. The number portion identifies the test sequence. Tests and related faults carry the same test sequence number.

A1phabetical suffixes, N or G, are used to denote a program no-go flag or program-go-condition. The number of times a N or a G is repeated is a history of decisions made within the test sequence. A numeric suffix, if used, denotes a decision that is not based upon a program no-go flag; i.e., an inprocess self-test fault. The numeric suffix and alphabetical suffix are separated by a point symbol.

- SELF-TEST This column contains test or fault description, LCU front panel indications, and corrective action instructions. The self-test program listing is divided into parts in accordance with the portion of the test set being tested. Each division of the listing is titled and the title enclosed in a box made up of asterisks. The test/fault description is on the same line as its test/fault number. If more than one line is required for the description, the second and subsequent lines are not indented. Signal routing information is subscripted. А description of test set operation for each test or fault is indented two spaces. The chart that follows. indented nine spaces, lists the LCU front panel TEST STATUS indications and REGISTERS display with the assemblies to be replaced for the listed indications.
- provides REMARKS The remarks column additional information for the listed test/fault data. A remarks entry in line with a test/fault test set operation description provides information about the state of the test set during the

## Entry

Abbreviations

or Symbol

EIP

ΕN

EOP

EOPA

EOTF

EIPA

EMJT

Definitions

External input from A register

External output from A register

External input

Instruction code

External output

Instruction code

Enable

operation. A remarks entry in line with an assembly replacement listing gives further information concerning the cause of a malfunction should assembly replacement fail to correct the malfunction.

#### b. Abbreviations and Symbol Definitions

b. Abbreviatio	ns and Symbol Definitions	EOIF	Instruction code
		EVPC	Instruction code
Abbreviations	Definitions	EXM	External memory
or Symbol		EXMW	External memory word
		EXT	External
AANC	Instruction code	FF	flip-flop
ADDR	Address	FUNC	Function
AMP	Amplifier	GDATC	Control-indicator signal
AND	Logic "AND" function	GEN	Generate
AREG	A register	GINT	Instruction code
AUTO	Automatic	GREG	G register
AZ. C.	Computer analog signal	G. S.	Computer analog signal
BCLK	B register clock	GSPU	Gyro stabilized platform unit
BNMJ	Instruction code	GSP1	Instruction code
BR	Branch	GSP3	Instruction code
BREG		NEX	
	B register		Hexidecimal
BRMJ	Instruction code	HMFL	Instruction code
BRNO	Instruction code	IBT	Instruction bit time
В. Т.	Bit time	IN	Input
BUFF	Buffer	INB	Inhibit
CANT	Cannot	INCM	Instruction code
CC	Clock counter	INH	Inhibit
CCBT	Count complete bit time	INMX	Input multiplexer
CFLG	Computer flag	INST	Instruction
СН	Check	INTF	Interface
CHAN	Channel	I/O	Input/Output
CIAR	Character	LACW	Instruction code
CIU	Control indicator unit	LCU	Logic conditioning unit
CIU1	Instruction code	LD	Load
CIU2	Instruction code	LDAB	Instruction code
CL	Clear	LDCA	Instruction code
CLK	Clock	LDCE	Instruction code
CMAB	Instruction code	LDC1	Instruction code
CMPLT	Complete	LDCT	
	•		Instruction code
CNTR	Counter	LDCP I	Instruction code
COIMP	Computer	LDMB	Instruction code
CP	Computer register	LDS1	Instruction code
CREG	C register	LOC	Location
D. A.	Computer analog signal	LQJD	Instruction code
DC1U	Instruction code	L. S.	Computer analog signal
DEF	Defines	LSB	Least significant bit
DEIP	Instruction code	LSD	Least significant digit
DEV	Computer analog signal	LSHD	Least significant hexidecimal digit
DIFF	Different	LSOD	Least significant octal digit
DIHR	Discrete input word-holding register	LVWC	Instruction code
DISC	Discrete	LXMB	Instruction code
DNCU	Instruction code	MABC	Major branch comparator
DOWD	Discrete output word	MAJ	Major
DR	Driver	MAL	Malfunction
DSPL	Display	MATR	Major test address register
DSTS	Instruction code	MDPL	Map display bit field
EA	Computer register	MEM	Memory
EB	Computer register	MFIL	Instruction code
		MIBC	
EIOPB	External input/output from/to B register		Minor branch comparator
		MIN	Minor
		MISC	Miscellaneous

MSB

Most significant bit

Abbreviations or Symbol	Definitions	Abbreviations or Symbol	Definitions
MSD	Most significant digit	SAT	Saturation
MSHD	Most significant hexidecimal digit	SB	Significant bit
MSOD	Most significant octal digit	SCU	Signal conditioning unit
MTC	Minor test counter	SCWM	Instruction code
MTW1	Miscellaneous test word number 1	SDRG	Instruction code
MUX	Multiplexer	SEG	Segment
MVET	Instruction code	SEL	Selected
NET	Network	SHT	Short
NOOP	Instruction code	S1CP	Instruction code
NOPE OCT	Instruction code	S1G S1IC	Significant
OP(S)	Octal Operation(s)	S1C S1M	Instruction code Simulated
OR OR	Logic "OR" function	S1NC	Instruction code
PE	Parallel enable	S1NM	Instruction code
PJB	Computer buffered EB register	S1NP	Instruction code
PLS	Pulse	S1OC	Instruction code
POR	Power on reset	SLMA	Instruction code
POSFIX	Position fix	SLMC	Instruction code
PREAMP	Preamplifier	SMFL	Instruction code
R&C	Read and compare	SREM	Instruction code
RCAA	Instruction code	SRT	Start
RCAM	Instruction code	SS1D	Instruction code
RCAQ	Instruction code	SS10	Instruction code
RCCA	Instruction code	ST	Self-test
RCCE	Instruction code	STATE 2	Tape search fast reverse
RCC1 RCCM	Instruction code	STATE 3	Tape search slow forward => approach to found location
RCCP	Instruction code Instruction code	STCL	Instruction code
RCDW	Instruction code	STOP	Instruction code
RCEA	Instruction code	STP	Stop
RCEB	Instruction code	STREG	Self-test register
RCEX	Instruction code	SW	Switch
RCFM	Instruction code	ТА	Test address on tape
RCMA	Instruction code	TAC	TACAN
RCMB	Instruction code	TRANS	Transfer
RCM1	Instruction code	TS	Tape search => search for tape address location
RCM2	Instruction code	TST1	Instruction code
RCNC	Instruction code	TST2	Instruction code
RCNU	Instruction code	TST3	Add
RCPC RCPJ	Instruction code	UNBR UNC	Instruction code
RCVVI	Instruction code Instruction code	VS	Unconditional Versus
RCW1	Instruction code	WD	Word
RCW2	Instruction code	WD W1	Word 1
RCW3	Instruction code	x	Unspecified
RCXM	Instruction code	<	Less than
REC	Receiver	>	Greater than
REG	Register	=	Equals
REPL	Replace	$\rightarrow$	Data path (from to)
REQ	Required	@	At (as a punch tape code, address character)
REV	Reverse	ε	And (as a punch tape code, end of data)
RICP	Instruction code	/	And/or (as a punch tape code, instruction
RIIC	Instruction code		character)
RIM	Register input multiplexer	#	Number (as a punch tape code, data)
	Instruction code	=>	Implication
RINM RINP	Instruction code Instruction code	$\Phi$ D	Phase D
RINP	Instruction code		
RMBA	Instruction code	B-3. How to	Use the Self-Test Program Listing
ROM	Register output multiplexer		a a a a a a a a a a a a a a a a a a a
RSET	Instruction code		g is a description of the self-test program listing as it
RS1D	Instruction code	relates to test	t set self-test
RS10	Instruction code		

operation. An excerpt from the self-test program listing is described.

a. Starting with the entry in the TEST NO. column, 3651, (major test 36, minor test 51); the TEST/FAULT NUMBER column entry is test sequence 175, this number prefixed by the letter T denotes a test, the DEC1S1ON LEVEL column entry is a 1, which denotes the first decision level in test sequence 175. Arrival at decision level 1 in the program denotes that all previous tests have been successfully completed.

b. The test description listed in the SELFTEST PROGRAM column is the test instruction code RCMA and the result of the compare, a no-go flag. The test set operation is serially load the B register with hexidecimal number AFFFFFFF and read and compare the memory address (MA) lines with the A register. When the no-go flag is achieved, branch to test no. major 36 minor 58. Arrival at test no. major 36 minor 58, which is test sequence 176, denotes that test sequence 175 was successfully completed. Non-arrival at test no. major 36 minor 58 indicates a go condition exists at test sequence number 175 because the no-go flag was not achieved. Therefore, this is the first decision level.

c. If, before the test set was conditioned to achieve a no-go flag during test sequence T175, the test set inprocess self-test detected a fault, the tape would stop. The test sequence number 1 75v would be prefixed by a F and suffixed by .1, indicating a fault location in test sequence 175 not based upon a self-test program no-go flag. this fault location is a decision level 2. The fault description is fault location within test sequence 175, not a programmed stop, and probable cause is RCMIA latch not reset. The LCU front panel indication is TEST STATUS TEST SET FAULT indicator lighted and REGISTERS display is 1000000. То correct malfunction, replace assembly 1A1A4A15.

d. If during test sequence T175 a no-go flag was not achieved, the program would not branch, but would step to test no. major 36 minor 53, test sequence T175.2. The test description is -test for a fault in read memory address (MA) enable (EN). The test set operation is compare the B register with the A register and branch to test no. major 36 minor 55 if a no-go is achieved.

e. If in test sequence T175.2 a no-go flag was achieved, the self-test program would branch to test no. major 36 minor 55. This is fault location F175.2.N, which is still part of test sequence 175.2. The N suffix denotes that in the previous test a no-go was achieved. The fault description is fault in RCMA instruction bit time (IBT) or latch. Test set operation is enable vertical parity check, stop tape, display the C register, and no-go light on. The LCU front panel indication is TEST STATUS NO GO lighted and REGISTERS indicator display is 1777777777. To correct malfunction, replace assemblies IA1A2A18, and/or 1A1A4A (15, 16).

f. If in test sequence T175.2 a no-go flag was not achieved and a go condition existed, the self-test program would not branch, but would step to test no. major 36 minor 54. This is fault location F175.2.G, which is still part of test sequence 175.2. The G suffix denotes that in the previous test a go condition existed. The fault description is read memory address (MA) fault. Test set operation is enable vertical parity check, stop tape, display the C register, and no-go light on. The LCU front panel indication is TEST STATUS NO GO indicator lighted and REGISTERS display is blank. To correct malfunction, replace assembly 1A1A4A15. If assembly replacement does not correct malfunction, the REMARKS column entry indicates logic term AAC017\* stopped at 1 may be cause of malfunction.

g. After correction of the malfunction, the operator will re-run the self-test program to insure test sequence 175 is successfully completed.

B-4

TESTIDECISION   TEST/FAULT _NO_1LEVELINUMBER		R ЕМАРКS
	PUNCH TAPE LEADER 12 INCHES LONG         PUNCH TAPE CODES - 20 70 F8 20 20 20 20 20 20 20 08 F8 08 00 B8 68 F8         00 F8 28 F8 00 08 F8 08 00 E8 A8 B8 00 00 00 00         00 F8 28 38 00 F8 28 88 00 20 20 20 00 E0 A0 F8 00 F8 28 38         00 F8 28 38 00 F8 88 F8 00 F8 08 00 F8 08 00 F8 08 00 F8 28 38         00 F8 28 38 00 F8 88 F8 00 F8 08 00 F8 08 00 F8 08 00 F8 28 38         00 F8 28 38 00 F8 88 F8 00 F8 00 00 00 00 08 F8 08         00 E0 A0 F8 00 F8 88 F8 00 F8 00 F8 00 00 00 00 F8 08         00 E0 A0 F8 00 F8 88 F8 00 F8 00 00 00 00 08 F8 08         00 E0 A0 F8 00 F8 00 F8 00 F8 00 00 00 00 08 F8 08         00 E0 A8 B8 00 88 A8 F8 00 68 A8 F8 00 68 A8 F8 00 20         20 20 00 E8 A8 B8 00 88 A8 F8 00 F8 08 00 F8 A8 58         00 E0 A8 B8 F8 00 F8 40 20 10 F8 00 88 A8 F8         00 88 88 F8 00 F8 40 20 10 F8 00         00 88 88 F8 00 F8 40 20 10 F8 00         00 88 88 F8 00 F8 40 20 10 F8 00         00 88 88 F8 00 F8 40 20 10 F8 00         00 88 88 F8 00 F8 40 20 10 F8 00	LEADING HEADER
	******	
* *	INITIAL CONFIDENCE TESTS (FAULT ISOLATION)	* *
* *******	********	*
0 00 0 01 0 02 0 03 0 04 0 05 0 06 0 07 0 08 0 07 0 08 0 09 0 10 0 11 0 12 0 13 0 14 0 15 0 16	PUNCH TAPE LEADER 24 INCHES LONG PUNCH TAPE LEADER 36 INCHES LONG	
0 10 0 17 0 18 0 20 0 21 0 22 0 22 0 23 0 24 0 25 0 26 0 27 0 28 0 29 0 29 0 31	PUNCH TAPE LEADER 36 INCHES LONG	
0 32		

ITESTIDECISION   TEST/FAULT   I NO. I LEVEL   NUMBER	SELF-TEST PROGRAM	REMARKS
00 34		
00 35		
00 36		
00 37		
00 38		
00 39		
00 40		
00 41		
00 42		
00 43 00 44	PUNCH TAPE LEADER 36 INCHES LONG	
00 45	FORCH TAPE ECANER SO INGLES CONS	
00 46		
00 47		
00 48		
00 49		
00 50		
00 51		
00 52		
CO 53 OD 54		
00 55	PUNCH TAPE LEADER 36 INCHES LONG	
00 56		
00 57		
00 58		
00 59		
00 60		
00 61		
00 62		
00 63 00 64		
00 65		
00 66	PUNCH TAPE LEADER 36 INCHES LONG	
00 67		
00 68		
00 69		
00 70		
00 71 00 72		
00 72		
00 74		
00 75		
00 76		
00 77	PUNCH TAPE LEADER 36 INCHES LONG	
00 78		
00 79		
00 80 00 81		
00 82		
00 83		
00 84		
00 85		
00 86		
00 87		

TESTIDECISION   TEST/FAU		REMARKS
0 88 0 89 0 90	PUNCH TAPE LEADER 36 INCHES LONG	
91		
92 93		
94 95		
) 96 ) 97		
) 98 ) 99	PUNCH TAPE LEADER 36 INCHES LONG	
	LOAD A REGISTER WITH A381F INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBF7F0FFF	INH MEM LD BREG DN CMA121,
	ATTAIL SEE TEST MODE 2 LOAD SEET TEST REGISTER WITH OTOTTOTT	ROM->OSPL/INH MEM LO BREG
	DSPL = 1000000000 LOAD A REGISTER WITH 40000000	<b>k</b>
	PUNCH TAPE LEADER 48 INCHES LONG	
	DSPL = 1111111111	
	LOAD A REGISTER WITH 49249249 Punch tape leader 48 inches Lons	
	DSPL = 2222222222	
	LOAD A REGISTER WITH 92492492 Punch TAPE leader 48 Inches Long	
	DSPL = 333333333333	
	LOAD A REGISTER WITH DR6DB6DB Punch tape leader 48 inches Long	
	DSPL = 444444444	
	LOAD A REGISTER WITH 24924924 Punch TAPE LEARER 48 INCHES LONG	
	DSPL = 555555555	
	LOAD A REGISTER WITH 2086D86D PUNCH TAPE LEADER 48 INCHES LONG	
	DSPL = 666666666	
	LOAD A REGISTER WITH 36086086 PUNCH TAPE LEADER 48 INCHES LONG	
	ESPL = 777777777	
	LOAD A REGISTER WITH BEFEFEFE PUNCH TAPE LEADER 24 INCHES LONG	
3 00	PUNCH TAPE CODES - &C	FORMAT ERROR: TWO ADDRESS Char, then end of data C
	PUNCH TAPE LEACER 12 INCHES LONG	

ITESTIDECISION   TEST/FAULT  _NO.1LEVELLNUMBER	I SELF-TEST PROGRAM	REMARKS
13 01	PUNCH TAPE CODES - 19 18 &C	IBT TEST: INVALID Instruction = octal 211
13 02	PUNCH TAPE CODIS - #0 /F /6 80	FORMAT ERROR: DATA THEN INSTRUCTION
13 03	PUNCH TAPE CODES - /E /8 &C	IBT TEST: S.T. NOOP
13 04	PUNCH TAPE CODES - /0 /8 &C /1 /C &C	IBT TEST: S.T. NOPE, SMFL + MSD
13 05	INITIATE SELF TEST MODE 3-COMPARE SELF TEST REGISTER TO A REGISTER WITH REPEAT PATTERN: 1	CHECK LOADING OF A REG VS. SELF TEST REG
13 06	ENABLE VERTICAL PARITY CHECK END OF MAJOR TEST	

4

TESTIDECISION   TEST/FAULT    _NQ+L_LEVEL_LNUMBER	SELF-TEST PROGRAM	REMARKS
29 00	GENERATE NO OPERATION CODE OCTAL 000 PUNCH TAPE LEADER 36 INCHES LONG	
32 00	GENERATE NO OPERATION CODE OCTAL 000 PUNCH TAPE LEADER 36 INCHES LONG	
44 00	GENERATE NO OPERATION CODE OCTAL 000 PUNCH TAPE LEADER 36 INCHES LONG	
55 00	GENERATE NO OPERATION CODE OCTAL 000 PUNCH TAPE LEADER 36 INCHES LONG	
66 00	GENERATE NO OPERATION CODE OCTAL 000 PUNCH TAPE LEAPER 36 INCHES LONG	
78 00	GENERATE NO OPERATION CODE OCTAL COO PUNCH TAPE LEADER 36 INCHES LONG	
89 00	GENERATE NO OPERATION CODE OCTAL COO PUNCH TAPE LEADER 36 INCHES LONG	
	PUNCH TAPE CODES - 21 21 29 /0 /0 &C PUNCH TAPE LEADER 36 INCHES LONG END OF MAJOR TEST	ADDR = 91, 3ADDR = FORMAT Error, Nope

5

TESTID	LEVEL	NUMBES	SELF-TEST PROGRAM	I REMARKS	
		**************************************	}*************************************	**************************************	
		*	AUTO BRANCH TESTS	*	
		* ********	**************************************	÷ ******	
	1		ENABLE LOW LEVEL ON GTCOOI* RESET INHIBIT INCREMENT OP FLAG & ENABLE SELF TEST CIU CLOCK MODE (GTCOO3*)	AVGID ENABLE OF S. TEST DURING LOAD REG	
	1	τı	TEST UNC. BRANCH WITHIN MAJOR TO MINOR 1 LOAD A REGISTER WITH 00102	BRANCH ADDR SET UP Variable branch	FDR
0 00	2	F10.3 F11_2	FAULF LOCATION WITHIN TEST TI (NOT A PROGRAMMED STOP)		
			INDICATORS I DISPLAY I	STATE 2 & SEL ADDR	AT 02 00
		T1(CONT.)	BRANCH TO ADDRESS LOCATION IN A REGISTER	VARIABLE BRANCH, P	ART OF F1
				IF FROM	G <b>Π</b> ΤΟ
				1) INITIAL CONF. 2) maj 12 min 3 3) maj 1 min 80	MINOR MINOR MINOR 1
	2	T1.11	TEST OF UNC. BRANCH DUT OF MAJOR WITH NO BRANCH MODE IN T1 BRANCH TO MAJOR 2 MINOR 19		
	3	F1.11.1	TEST OF DIFF. SCU INST. & FAULT LOCATION READ & COMPARE PJB LINES WITH 5555555 INITIATE SELF TEST MODE 3-COMPARE SELF TEST REGISTER TO A REGISTER WITH REPEAT PATTERN: 1 LOAD A REGISTER WITH 55555555 STOP FAPE, DISPLAY C REGISTER, NO-GO LIGHT ON		

TESTIDECISION   TEST/FAUL	SELF-TEST PROGRAM	I REMARKS I
	INDICATORS       1       DISPLAY       I       REPLACE ASSEMBLIES         (TEST SET FAULT         2000 2A1A1A02       I       I2A1A2A09         ITEST SET FAULT         100001AA1A09       I         ITEST SET FAULT         100001AA1A09       I         ITEST SET FAULT         100001AA1A09       I         ITEST SET FAULT         100012A1A1A02       I         IND GO       1       BLANK       IPROCEED PER PARAGRAPH 3=120         INO GO       12525252525211A1A1A(4,6)       I         INO GO       13725252525211A1A1A(4,6)       I         INO GO       13725252525211A1A1A(4,6)       I         INO GO       13725252525211A1A1A(4,12)       I	NO LOAD OF B REG WITH RCPJ NO "END OF DATA" TO SCU NO "END OF DATA" TO ZAIA2 SHORT DATA ACTIVE NO BRANCH MODE, RCPJ OK
00 01 1 T2	TEST OF BNMJ WITHOUT NO-GO PUNCH TAPE CODES - /F /7 #9 #2 #0 &C BRANCH TO MAJOR OO MINOR 28 ON NO-GO	INCM 029; GO TO MIN 29 IF BRMJ NOT RESET
1 T3	ENABLE VERTICAL PARITY CHECK TEST OF BRANCH ON "NO-GO" WITH "ND-GO". TEST SKIP MINORS LOAD A REGISTER WITH 07900 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBF7E4F7F PUNCH TAPE CODFS - /5 /1 #2 #0 #7 #0 &C	IF XPF362 S01 GD TO 79 NOT 7 ROM->DSPL, CLK RUN TAPE STP, SIM ND-GO, ROM->RIM BNMJ 2 7 - MAJ 2 IS ADDED TO TEST BRANCH WITHIN MAJ FUNC
2 T3.6	TEST BNMJ WITH "NO-GO FLAG" SET UP SERIALLY LOAD THE B REGISTER WITH A COMPARE THE B REGISTER TO AF BRANCH TO MAJOR OO MINOR 54 ON NO-GO	C = 0F000000
3 73.6.5	CHECK OTHER BRANCH ON NO-GO INST. BRNO BRANCH TO MAJOR 2 MINOR 74 ON NO-GO	
4 T3.6.G.2	TEST IF BNMJ LATCH IS SET LOAD A REGISTE® WITH O BRANCH TO MAJOR 2 MINOR 22	
5 F3.6.G.2.3	NOT A NORMAL FAULT LOCATION ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	

TESTIDECISION	I TEST/FAULT	J SELF-TEST PROGRAM	I REMARKS
		I INCICAIORS I DISPLAY I REPLACE ASSEMBLIES	
0 02 2	F3.4	CANT SKIP MINORS ENABLE VERTICAL PARITY CHECK INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBF7F0FFF STOP TAPE	ROM->DSPL
		IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI NONEI34XXXXXXI2AIA2AI9.10.12)	
00 03 2	F1•3 F3•2	FAULT IN BIT OF BRANCH ADDR FIELD TO MINOR COMPARATOR, BIT 22 OR BIT 23 ENABLE VERTICAL PARITY CHECK LOAD A REGISTER WITH 00502 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH DEBETEDEFF STOP TAPE	ROM->DSPL
		  NONE   24XXXXXX  A A A A0	BIT 22 DF A REG DR RDM ACTIVE 6TH DR 7TH SIG BIT OF MIRC
		II2A1A2A11I	OR MTC
0 04 1		MANUAL MODE PROGRAM LOCATION- BRANCH TO VERIFY TESTS "VERIFY ENTIRE TAPE" Section Define EIP data field as present contents of a register Branch to Major oo Minor 15	FROM VARIABLE BRANCH MIN 00
		BRANCH TO MAJOR OO MINOR 15	THIS INST WILL BE BRANCHED OVER BUT DEIP LATCH WILL RESET BR ADDR IN ARES => B TO MIN 100
00 05 2	F1.4 F3.3	FAULT IN BIT OF BRANCH ADDR. FIELD TO MINOR COMPARATOR, BIT 22 OR BIT 23 ENABLE VERTICAL PARITY CHECK LOAD A REGISTER WITH 00302	
		INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBF7FOFFF STOP TAPE	RUM-SUSPL

TESTIDECISION			REMARKS
		IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI NONEI4XXXXXI2A1A1A(23.24) NONEIAXXXXXI2A1A1A(12.23.24) III NONEI_4XXXXXI2A1A1A(12.23.24) II_I NONEI_4XXXXXI1A1A1A01 II_4XXXXXIIA1A1A01	BIT 22 OF ROM INACTIVE BIT 23 DF A REG DR ROM ACTIVE 6SB OR 7SB OF MIBC, OR MTC
00 06 2	F22.1	CANT BRANCH FORWARD DUT OF MAJOR ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT DN	
		IINDIC4TORSI_DISPLAYIBEPLACE_ASSEMBLIESI IND_GOIBLANKIPROCEED_PER_PABAGRAPH_3-12DI	
0 07 1	Τ4	CHECK RESET OF IST2 PUNCH TAPE CODFS - /F /7 #9 #2 #0 &C	INCM 029; GO TO MIN 29 IF
0 08		SERIALLY LOAD THE B REGISTER WITH A30F0F0F	BNMJ NOT RESET Set up addr to branch to if TST2 FF Kyr702 NDT RESET
2	F4.2	FAULT LOC WITHIN TEST 14, NOT A PROGRAMMED STOP- IN-PROCESS FAULT Detected associated with LDAB Func	
		IINDICAIORSI_DISPLAYIBEPLACE_ASSEMBLIESI IIESI_SET_EAULI_I40000012A1A1A(6.25) IIESI_SET_EAULI_I20000012A1A1A12.5.6.8.10.13) IIESI_SET_EAULI_I100001PROCEED_PER_PARAGRAPH_3-12DI	
1	T4 (CONT )	PUNCH TAPE CODES - /5 /1 #F #F #F #4 #F #F #0 #0 #4 #2 &C	BNMJ 42 IF KYR702* @ 1. IF KYR702* @ 0,DATA->STREG = SIM NO-GO, BRANCH TO PREVIOUS ADDR IN AREG
1	T5	TEST FOR SELF TEST REG NOT RESET INITIATE SELF TEST MODE 2-RETAIN PREVIOUS BIT PATTERN IN SELF TEST REG. BRANCH TO MAJOR OO MINOR 62 ON NO-GO	
1	т6	CHECK RESET OF LCU SECTION OF STREG ENABLE CONTROLLED TIMING PULSE INTERVAL 1 ON GTCOOI*	
2	F6.1	FAULT LOC WITHIN TEST TO- SELF TEST REG NOT RESET OR CLK COUNTER ERROR	

TE ST   0   _NQ • L	DECISION LEVEL	I TEST/FAULT	ELE-TEST PROGRAM	I REMARKS
			I INDICATORS I DISPLAY I BEPLACE ASSEMBLIES	KYRO23 FF NOT RESET
			11A1A3A23   IEST_SET_FAULI_1200000011A1A3A16+7+8+9+101	I CLK COUNTER ERROR
	1	τ7	CHECK RESET OF TST1 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFF4FFF BRANCH TO MAJOR OO MINOR 10 ON NO-GO	STM NO GO -SHOULD RE PULCA
	1	т.8	TEST OF 2ND & BRD SIG BIES OF MTC TO MIBC OR AT MIBC SERIALLY LOAF THE B REGISTER WITH ABOFOFOF LOAD A REGISTEP WITH 10000000 BRANCH TO MAJOR OO MINOR 60	
00 09	2	F1.5	558 OF BRANCH ADDR FIELD ACTIVE ENABLE VERTICAL PARITY CHECK LOAD A REGISTER WITH 00102 INITIATE SELF TEST MODE 2-LOAD SELF TEST RESISTER WITH OFBF7F0FFF STOP TAPE	ROM->RIM
			I_INDICATORSI_DISPLAYI       REPLACE_ASSEMBLIES         NONE       4XXXXXX/IAIAIAOI         II2AIA2AII       I2AIA2AII         NONE       44XXXXXX/2AIAIA(12,23,24)         II       II	558 OF MTC OR MIBC     311 24 OF A REG OR ROM
GO 10	2	F7.1	FAULT IN TST1 RESET OR SELF TEST REG PE ENABLE VERTICAL PARITY CHECK STOP TAPE, FISPLAY C REGISTER, ND-GO LIGHT ON	
			iINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES IND_GCIBLANKI2A1A3A114.15.161	-   
OC 11	2	F1.6	4SB OF BRANCH ADDR FIELD ACTIVE ENABLE VERTICAL PARITY CHECK LOAD A REGISTER WITH 00102 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBF7F0FFF STOP TAPE	ROM->RIM

	SION   TEST/FAULT VELLNUMBEB		I REMARKS
		IINDICATORSI_DISPLAYI	† 458 OF MTC OR MIBC 1 1 BIT 25 OF A REG OR ROM
00 12 1		MANUAL MODE PROGRAM LOCATION+ BRANCH BACK TO MANUAL MEMORY CONTROL TESTS Maj 12 Branch to Major 2 Minor 10	FROM VARIABLE BRANCH MIN 00
00 13 1 00 14	τ15	TEST SIDC RESET OF TST2 AND RIOC RESET OF SIDC SET THE I/O COMPLETE FLAG (GTCO10*) RESET THE I/O COMPLETE FLAG (GTCO10*) BRANCH TO MAJOP OO MINOR 86 ON NO-SO INITIATE SELF TEST MUDE 2-LOAD SELF TEST REGISTER WITH OFBFFF4FFF BRANCH TO MAJOP OO MINOR 72 ON NO-GO BRANCH TO MAJOP OO MINOR 97	RESET TST2 USED IN 113 RESET SLOC TEST IF TST2(SIM NO-GO) IS RESET SIM NO-GO IF SLOC NOT RESET GO TO MIX 97 INSTEAD OF MIN 72 = T15
00 15		SP AR E	
00 16 1 CC 17		NOT A TEST LOCATION- BRANCH HERE FROM MIN 32 IF TI8 PASSED BRANCH TO MAJOR OO MINOR 25	GD TD T19
06 18 2	F9.1	FAULT IN MSB OF MTC TO MIPC, OR IN MSB OF MIBC ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C RESISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES [NO GO BLANK1A1A1A25 ]	ł
00 19 3	F1.11.3	OPEN INPUT AT GATE BPJ031, "OR" OF BRANCHES ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, ND-SO LIGHT ON IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES IND_GDIBLANKI2A1A2A12	
00 20 2	F8.1	FAULT IN 258 OF MTC TO MIRC, OR IN 258 OF MIBC ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	

TESTICECISION   TEST/FAULT		2EMARKS
	IINCIGAIORSI_EISPLAYIBEPLACE_ASSEMBLIES IND COI_BLANK (1A1A1A11 IIZA142A1Q	- - f - 1 _ 1
CO 21 2 F1.7	35B OF BRANCH ADOR FIFLD ACTIVE ENAPLE VERTICAL PARITY CHECK LUAD A REGISTER WITH 00102 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBF7F0FFF STOP TAPE	ROM -> DS°L
		3SB OF MTC OR MIBC _    BIT 25 OF A REG OR ROM
	ILLL	_1 ACTIVE
00 22 5 F3.6.3.2.1	FAULT IN BRANCH ON NO-GO "OR" FUNCTION ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES (ND_GO170000000012A1A2A(6,12)	   !
00 23 1 00 24	NOT A TEST LOCATION- BRANCH HERE FROM MIN 26 IF T18 PASSED BRANCH TO MAJUR OO MINOR 52	30 TO T19
00 25 1 T19 00 26	TEST 658 OF MIRC, ENABLE DF STATE 2 BRANCH TO MAJOR OO MINOR 23	
GO 27 2 F19.1	658 DF MIRC CAN NOT ENABLE STATE 2 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICAIDRSI_DISPLAYIREPLACE_ASSEMBLIES IND_GOBLANKI2A1A2A11	- _  _  BPJ261* S@1
0C 28 2 T2.2	CHECK STATE OF "NO-GO" FLAG, ATTEMPT RESET SERTALLY LOAD THE B REGISTER WITH AAAAAAAA Compare the B register to the A register Branch to Major oo Minor 49 on ND-GO	
3 F2.2.G	ND-GO FLAG WAS RESET, BUT INITIALLY WAS SET ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, ND-GD LIGHT ON	

TESTIDECISION	TESTZEAULT I NUMBER		I REMARKS
		IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIES INO GO ILANK [2A1A1A04 II_OR IINGRUISENANCE INO_GOIXXXXXXXXXXZA1A2A17	
00 29 2	F 2.1 F4.1 F11.1 F14.1	BRANCH LATCH NOT RESET PUNCH TAPE CODES - /F /7 /1 /0 &C ENABLE VERTICAL PARITY CHECK	3 INST CHAR = FORMAT ERROP, 1ST 2 = INCM, 2ND 2 = MIDO, 4TH CLEARS VERTICAL PARITY
		INTELECTION CREEKEN NO-GO LIGHT ON I INCICATORS L DISPLAY I REPLACE ASSEMBLICS ITEST SET FAULT I 4000000000024A142406 I I DR I DR I DR I DR	APJ045*
00302	F4.4	IST2 FF "KYR702" NOT RESET ENABLE VERTICAL PARITY CHECK STOP TAPE, PISPLAY C REGISTER, ND-GO LIGHT ON A <u>INDICATORS I DISPLAY</u> I <u>REPLACE ASSEMBLIES</u> IND GD	- 1 1
00 31 1 00 32	T1 8	TEST 3SE OF MIRC, ENARLE OF STATE 2 BRANCH TO MAJUR OO MINOR 16	
CO 33 3	F10.2N	UNBR IBT OR LATCH INACTIVE ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINCICATORSLDISPLAYIREPLACE_ASSEMBLIES (NO_3DLBLANKI2A1A2A16.12)	
00 <b>34</b> 1 00 <b>3</b> 5		NOT A TEST LOCATION- BRANCH HERE FROM MIN 76 IF TIL PASSED ENABLE VERTICAL PARITY CHECK BRANCH TO MAJOR OG MINOR 82	30 TO T12
00 36 2	F18.1	358 OF MIRC CAN NOT ENABLE STATE 2 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, ND-GD LIGHT DN	

TESTIDECISION   TEST/FAULT	I SELF-TEST PROGRAM	REMARKS
	IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES IND_GOIBLANK12A1A2A10	- _1 _1 BPJ531* S91
00 37 1 T17 00 36	TEST 558 OF MERC, ENABLE OF STATE 2 BRANCH TO MAJOR OO MINOR 31	
00 39 2 F17.1	558 OF MIRC CAN NOT ENABLE STATE 2 ENABLE VERTICAL PARTTY CHECK STOP TAPE, DISPLAY C REGISTER, NO-SO LIGHT ON	
	IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIES INO_GOIELANKI2A1A2A11	_  _  RPJ251* S@1
00 40 2 Fe.2	2SB OF MTC TO MIRC OR IN 2SB OF MIBC ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
	I INCICATORS I DISPLAY I REPLACE ASSEMBLIES.	 
00412 F1.8	258 OF BRANCH ADDR FIELD ACTIVE ENABLE VERTICAL PARITY CHECK LOAD A REGISTER WITH 00102 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBF7F0FFF STOP TAPE	ROM -> DSPL
	IINDICAIORSI_DISPLAYIBEPLACE_ASSEMBLIES NONE   4XXXXXX(IAIAIAII  I2AIAIAI0 NONE   404XXXXXX(2AIAIA(12,21)	L 259 OF MTC OR MIBC
	111	_! ACTIVE
00 42 2 T4.3 00 43	TEST RESET OF IST2 WITH COMPARE (RCEB) READ & COMPARE THE EB LINES WITH A0000000 BRANCH TO MAJOR OF MINOR 44 ON ND-SD	CHECK IF RCEB RESET NO-GO OF TST2
3 F4.3.G	FAULT IN LDAB LATCH , IBT, INPUT TO "CARO36" OR INST DECODE MATRIX ENABLE VERTICAL PARITY CHECK PUNCH TAPE CODES - /D /O &C	INVALID INST = 0/1/5 OCTAL-
	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	TEST DECODE MATRIX

TESTIDECISION			REMARKS
		I INDIGATORS I DISPLAY I REPLACE ASSEMBLIES TEST SET FAULT I 40/2A1A1A(1,2) I 2A1A2AQ2 IND_CO I RLANK IPROCEED PER PARAGAPH 3-12D	
00 44 3	77 7 8		( FADE) IN INST DECODE MARKE
)0 45	(++) +V	RESET TST2 WITH SIDC SET THE I/O COMPLETE FLAG (GTCO10*) RESET THE I/O COMPLETE FLAG (GTCO10*) BRANCH TO MAJOR OO MINUR 46 ON NO-30	RESET TST2 RESET SIDC
4	74.3.NG	LDAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH ABA200	STM ND-00 EA ADDR = 350 I/O REQ ACTIVE
5	F4.3.NGG	FARET IN MAANE CMAB LEAB" RESET OF TST2, DR MEARO36" UNABLE VERTICAL PARITY CHECK INITIATE SELF TEST MODE 2-LEAD SELF TEST REGISTER WITH OFBFFF07FF STOP TAPF, DISPLAY C REGISTER, NO-GO LIGHT ON	
		Indicators         DISPLAY         REPLACE ASSEMBLIES           NO GO         1777777712A1A1A(1,2)           1         12A1A3A15           NO GO         125777777712A1A1A01	AYR714* SD1
0046 è	74.3.NN	ISOLATE FAULT WITHIN SELF TEST CONTROL, TST1 RESET OF SELF TEST REG INITIATE SELF TEST MODE 1-RETAIN PREVIOUS BIT PATTERN IN SELF TEST RES BRANCH TO MAJOU OF MINOR 64 ON NO-30	
5	F4.3.NNG	FAULT IN RESET OF TST2 ENABLE VERTICAL PARTLY CHECK STOP TAPE, DISPLAY C REGISTER: NO-GO LIGHT ON	
		I INDICATORS I DISPLAY I SEPLACE ASSEMBLIES	
00 47 1 00 48		NOT A TEST LOCATION- BRANCH HERE FROM MIN 53 IF /20 PASSED BRANCH TO MAJOR OO MINDR 66	60 TO T2)
00 49 3	T2.2.N	CHECK OTHER BRANCH ON NO-GO, 8000 BRANCH TO MAJOR O - MINOR 89 ON NO-GO	

		TEST/FAULT		REMARKS
	4	F2.2.NG	ND-GO INPUT AT INST DECODE GATE "CADO25" OPEN ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT UN	
			INDICATORS I DISPLAY I BEPLACE ASSEMBLIES	
0 50 0 51			SP AR E SP AR E	
0 52 0 53	1	T2 0	TEST 458 OF MIPC, ENABLE STATE 2 Branch to majop og minor 47	
00 54 00 55	3	T3.6.N	N CHECK FOR ACTIVE MEMOPY CONTROL SERIALLY LOAD THE B REGISTER WITH AAAAAAAA IMITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH DEBEFIOFEF SET THE I/O COMPLETE FLAG (GTCOIO*) RESET THE I/O COMPLETE FLAG (GTCOIO*) COMPARE THE B REGISTER TO THE A REGISTER BRANCH TO MAJOR 2 MINOR 50 BRANCH TO MAJOR 00 MINOR 50	ALL MEMORY LOAD B RES ACTIV Reset TST2 Reset Sidc
				GO TO (CO)Y3.6.441 (MAJ 19 MIN 3) VIA MAJ 2 MIN 4
n 56			SPARE	
0 <b>57</b>	2	F20.1	45B OF MIBC INACTIVE ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NU-GO LIGHT ON	
			INDICATORS I DISPLAY I BEPLACE ASSEMBLIES NO GO I BLANK IIAIAIAII I IZAIAZAIQ	   CPJ2∆1≄ S@1 
00 58 00 59	4	¥3.6.NS	CHECK STATE OF GTC001* READ & COMPARE MISCELLANEOUS WORD 1 WITH A00000CO LOGICALLY 'AND' C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS BRANCH TO MAJOR OO MINOR 68 ON NO-GO	
	ö	T3.6.NGG	TEST RESLT OF GTCOOL* FOUND ACTIVE IN 13.6.NG, RESET WITH RCNC SET INHIBIT INCREMENT OF FLAG & ENABLE SELF TEST NOU CLOCK MODE (GTCOO3*) ENABLE CONTROLLED TIMING PULSE INTERVAL IC CONDITIONALLY ON GTCOOL* RLAG & COMPARE MISCELLANEOUS WORD I WITH AO LUGICALLY 'AND' C REGISTER AND ADOODOCO - RESULT IN 3 & C REGISTER BRANCH TO MAJOR OO MINUR 92 ON NO-GO	

TESTIDECISION			REMARKS
6,	F3.6.NGCG	PROBLEM IN RESET OF GLUCK CONTROL FF USING STCL ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		INDICATORS I DISPLAY I BEPLACE ASSEMBLIES NO 50 I BLANK IIAIA2A18 I IIAIA3A(12.13)	   
0 50 )	79	TEST MSB, 458, 558 OF BRANCH ADDR FIELD FOR INACTIVE, 858 FOR ACTIVE LOAD A REGISTER WITH 80	SET UP 8 OF 98 IN BRANCH ADDR TO CHECK FOR PASS T: MIN 60
0 61		LUAD A RECISTER WITH 09	SET UP 9 OF 98 IN BRANCH ADDR- WILL = 90 IF MISS N 60
		BRANCH TO ADDRESS LOCATION IN A REGISTER	
0622	F 5 . N	FAULT IN RESET OF SELF TEST REG ENABLE VERTICAL PARITY CHECK LUAD A REGISTER WITH A30F0F0F STOP TAPE	
		INDICATORS   DISPLAY   REPLACE ASSEMBLIES  NONE   12430360741712A1A3A(15+16)  NONE   BLANK   2A1A1A(4+7)	GYR707 Sa0 DR IYR717* Sa1
0 63 5	F4 .1.NGN	"RESET LATCHES" ACTIVE ENABLE VERTICAL PARITY CHECK STOP TAPE: DISPLAY C REGISTER, NO-GO LIGHT ON	
		IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES NO_GQIBLANKI2A1A1A(1+6+17)	
064 5	F4.l.NNN	FAULT IN RESET OF SELF TEST REG ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C RECISTER, NU-GO LICHT ON	
		INDICATORS I DISPLAY I BEPLACE ASSEMBLIES	
0 65 1	Γ22	TEST OF BRANCH FORWARD OUT OF MAJ: SKIP MAJ 1, GO TO HAU 21 VIA MAJ 2 MIN 6	1
		ENABLE VERTICAL PARITY CHECK BRANCH TO PAJOR 2 MINOR 6	
0 66 1	T21	TEST 7ST AF MIRC, FWARLE STATE 2	

TESTIDECISION			REMARKS
		I	AATO91 530
0 75 1	711	TEST BRANCH IN STATE 2 WITHIN MAJ PUNCH TAPE CODES - /F /7 #9 #2 #0 &C	INCM 029, GO ID MIN 29 IF UNBR NOT RESET
00 76		BRANCH TO MAJOR 00 MINOR 34	
00 77 2	F16.1	2SB CAN NOT ENABLE STATE 2 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		IINDIGATOPSI_DISPLAYIBEPLACE_ASSEMBLIESI IND_GOIBLANKI2A1A2A10I	BPJ221* \$71
00 79 3	T8.3.1	PARTIAL BREG -> ROM ENABLE ACTIVE ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON IINDICATORSIDISPLAYIREPLACE_ASSEMBLIES1	
00 79 2	F3.7	END OF DATA ALWAYS ACTIVE AT BRANCH CONTROL, OR KYR722 S@O ENABLE VERTICAL PARITY CHECK LOAD A REGISTER WITH A0000000 INITIATE SELF TEST MODE 2-LOAD SELF TEST RESISTER WITH OFBF7F0FFF STOP TAPE	ROM->DSPL
		IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI NONFI2400000000012A1A1A02 III2A1A2A09 NONEI_74400XXXXI2A1A3A(15,16)	KYR722 S20
00 80 3	T3.1.N	CONFIRM FAULT IN BRANCH SHORT DATA EN SERIALLY LOAD THE B REGISTER FROM THE A REGISTER COMPARE THE B PEGISTER TO A80AAAAA LOAD A REGISTER WITH 08400 BRANCH TO ADDRESS LOCATION IN A REGISTER	
4	F3.1.NG	FAULT IN BRANCH SHORT DATA EN ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHY ON	

TESTIDECISION		I SELF-TEST PROGRAM	I REMARKS
		IINGICATORSI_DISPLAYIREPLACE_ASSEMBLIES IND_SCI_170000000012A1A2A06	AATO91 SD0
0751	<b>F1</b> 1	TEST BRANCH IN STATE 2 WITHIN MAJ PUNCH TAPE CODES - /F /7 #9 #2 #0 δC BRANCH TO MAJOR 00 MINOR 34	INCM 029, GO IU MIN 29 IF UNBR NOT RESET
0 77 2	F16.1	2SB CAN NOT ENABLE STATE 2 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAY	
0793	T8.3.1	PARTIAL BREG -> ROM ENABLE ACTIVE ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES IND_GOIXXXXXXXXXXI2AIAIAI9	1
0792	F3.7	END OF DATA ALWAYS ACTIVE AT BRANCH CONTROL, OR KYR722 SDO ENABLE VERTICAL PARITY CHECK LOAD A REGISTER WITH A0000000 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBF7FOFFF STOP TAPE I	1
0803	T3.1.N	CONFIRM FAULT IN PRANCH SHORT DATA EN SERIALLY LOAD THE B REGISTER FROM THE A REGISTER COMPARE THE R PEGISTER TO A80AAAAA LOAD A REGISTER WITH 08400 BRANCH TO ADDRESS LOCATION IN A REGISTER	
4	F3.1.NG	FAULT IN BRANCH SHORT DATA EN ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT DN	

TESTINECISION	I TEST/FAULT I NUMBER	I SELF-TESI PROGRAM	1 R. 46248
		INDIGATORS I DISPLAY I BEPLACE ASSEMBLIES NO 30   BLANK IZAIAIA28 I IZAIAZAIQ	1
0 81 2	F1.9	MSB OF BRANCH ADDR FIELD ACTIVE ENABLE VERTICAL PARITY CHECK LOAD A REGISIER WITH 00102 INTITATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBF/FOFFF STOP TAPE	R0M~>05PL
		INDICATORS       IDISPLAY       REPLACE_ASSEMBLIES         NONE       4XXXXXX11A1A1A25         I       12A1A1A10         INCNE       1004XXXXXX12A1A1A(12,21)	I MSB MIC->MIBC OR AT MIBC
0 32 1	T12	TEST OF BRANCH GN NO-GU OUT OF MAJ WITHOUT NO-GO BRANCH TO MAJUR O MINOR 85 ON NO-SO	
1	113	TEST OF BRANCH OUT OF MAJ ON NO-GO WITH NO-GO INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF4F7F BRANCH TO MAJOR OF MINOR 83 ON NO-GO	SIM NU-30, POSFIX PULSE Check
2	F13.1	FAULT IN BRNO IBT OR LATCH, OR TST2 ENABLE VERTICAL PARITY CHECK SET INHIBIT INCREMENT OP FLAG & ENABLE SELF TEST NOU CLOCK MODE (GTC003*) ENABLE CONTROLLED TIMING PULSE INTERVAL 20 ON GTC001* STOP TAPE	
		I INDICATORS I DISPLAY I REPLACE ASSEMBLIES NONE I BLANK I241434(15.16) NO_50 I BLANK 1241424(1.6)	_  KYR722 NOT RESET
00831	T14	TEST MSB OF MIBC, ENABLE STATE 2 PUNCH FAPE CODES - ZE ZE BRANCH TO MAJOR OO MINOR 13	INCM 029, GO TO MIN 29 I BRNO NOT RESEL
00 84 4	F3.1.NN	NOT A NORMAL FAULT LOCATION ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	

ITESTICECISION			REMARKS
		I INCIGATORS L DISPLAY I SEPLACE ASSEMBLIES IND_GDIXXXXXXXXXIPROCEED_PER_PARAGRAPH 3=13	
00 85 2	F12.1	NO GO INPUT TO B2NG IBT DECODE GATE "CADO24" OPEN ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I INDICATORS I DISPLAY I. BEPLACE ASSEMBLIES	
00 86 2	T15.1	CHECK SIDC->GTCO10*->MTW1 SET THE I/O COMPLETE FLAG (GTCO10*) READ & COMPARE MISCELLANEOUS WORD 1 WITH A LUGICALLY *AND* C REGISTER AND A0080000 - RESULT IN B & C REGISTER BRANCH TO MAJOR 00 MINOR 87 ON NO-GO	MASK ALL BUT GTC010*->001079
3	F15.1.G	FAULT IN SIDE RESET OF TST2 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHF ON I INDICATORS I DISPLAY I SEPLACE ASSEMBLIES IND GO I BLANK [241424]2 I 241434115-3-4+5-7]	CEC499* Sอง
OC 87 3	F15.1.N	SIDE IBT OR GEOID* DRIVER, INACTIVE ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYI3EPLACE_ASSEMBLIES IND_GOI200000012A1A2A(2,12,17,18)	1
00 <b>88</b> 00	F9.2	45B OF MIBC OR MIC TO MIBC INACTIVE ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, ND-GD LIGHT ON IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIES IND GOI_BLANKIATATATI I12A1A2A1Q	8 1 1
C/ E9 4	F2+2+NN	CANT RESET NO-GO FLAG ENABLE VERTICAL PARITY CHECK STOP TAPF, DISPLAY C REGISTER, MO-GO LIGHT DN	

	SION   TEST/FAULT /ELNUMBER		I REMARKS
		I_INDICAIORSI_DISPLAYIREPLACE_ASSEMBLIES NO GO I BLANK IZAIAIAO7 IIZAIAZAQ6	ł 1 1
00 90 2	F9.3	5SB OF MIBC OR MTC TO MIBC INACTIVE. OR 8SB ACTIVE ENABLE VERTICAL PARITY CHECK INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBF7F0FFF STOP TAPE	ROM->DSPL
		IINDICATORSL_DISPLAYL	
		II2A1A2A11I NONE11460400000012A1A1A(12+17)	1 1 1RA084# S@1
00916	F3.6.NGNN	FAULT IN SCU LSD INST DECODE Enable vertical parity check Stop tape, display C register, ND-G0 light on	
		I_INDICAIOBSI_DISPLAY_1BEPLACE_ASSEMBLIES NO_GOI200000012A1A2A(1,2)	1
00926	F3.6.NGGN	CANT RESET CLOCK CONTROL FF ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		I INDICATORS I DISPLAY I REPLACE ASSEMBLIES	- - - -
0932	F14.2	MSB OF MIBC CANT ENABLE STATE 2 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT DN	
		I <u>INDICATORS</u> I <u>DISPLAY</u> I <u>BEPLACEASSEMBLIES</u> INO.GOI <u>BLANK</u> IZALAZALO	   BPJ211≉ S∂1
00943 0095	T3.1.G	CONFIRM FAULT IN SHORT DATA EN AT 2A1A1 SERIALLY LOAD THE B REGISTER FROM THE A REGISTER COMPARE THE B REGISTER TO A94AAAAA LOAD A REGISTER WITH 09600 BRANCH TO ADDRESS LOCATION IN A REGISTER	
4	F3.1.GG	FAULT IN SHORT DATA EN AT 2A1A1 Enable vertical parity check Stop tape, display c register, ND-go light on	

		TEST/FAULT		I REMARKS I
			IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GDIBLANKI2A1A1A(12,17,28)I	
00 96	4	F3.1.GN	NOT A NORMAL FAULT LOCATION ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
			INDICATORSI_DISPLAYIBEPLACE_ASSEMBLIESI IND_GDIXXXXXXXXXIPROCEED_PER_PARAGRAPH_3=13I	
00 97	2	F15.2	FAULT IN RIOC LOGIC OR INST DECODE MATRIX ENABLE VERTICAL PARITY CHECK READ & COMPARE PJB LINES WITH A0000000 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	C REG = OFFFFFFF Should dspl ones in 5 reg
			INDICATORS E DISPLAY I BEPLACE ASSEMBLIES I IND.GO I 177777777712A1A2A112.17) IND.GO I BLANK IPROCEED.PES_PARAGRAPH_3=120	FAULT IN RIDC LOSIC FAULT IN INST DECODE MATRIX
00 98 CO 99	1	<b>T</b> 10	TEST OF UNCONDITIONAL BRANCH OUT OF MAJ TO SAME MAJ- ENABLE STATE 2 BRANCH TO MAJOR O MINOR 75 ON NO-GO	
	2	r10.2	TEST OTHER BRANCH OUT OF MAJ, BRNO INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF4FFF BRANCH TO MAJOP O MINOR 33 ON NO-GO	STM NO-GO
	3	F10.2.G	NOT A NORMAL FAULT LOCATION ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT DN	
			I_INDICAIORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GOIBLANKIPROCEED_PER_PARAGRAPH_3-13I	
00 00			MINOR 10G- BR LOGIC WILL INTERPRET AS MINOR OD=> RESET BR MODE OF MINOR 4 SERIALLY LOAD THE B REGISTER FROM THE A REGISTER LOAD A REGISTER WITH 066	RESET DEIP LATCH SET UP BR ADDR FOR MAJ 01 MIN 01

END OF MAJOR TEST

		***************************************
TEST DECISION   TEST/FAULT	SELF-TEST PROGRAM	REMARKS
I NO. 1 LEVEL 1 NUMBER 1		
· · · · · · · · · · · · · · · · · · ·		

****	****	****
*		*
*	MANUAL MODE SECTION	4
*		*
*	MAJORS 1 THRJ 18 REFER TO PARAGRAPH 13.3 FOR MANUAL TEST PROCEEDURE	*
*		*
****	***************************************	*****

÷		*
* TESTS IN MAJOR 01	INCLUDE: INSTRUCTION DECODE, DISPLAY, BRANCH, PANEL INDICATOR LOGIC, TAPE CONTROL	. *
★ AND MEMORY VERIFY	ENTIRE TAPE.	*
*		*
*		*
*	HERE ARE THREE ADDR OI WITHIN THIS MAJOR	*
*		净
*		*
<del>¢</del>	THERE ARE VARIOUS AUTO SECTION FAULT LOCATIONS WITHIN THIS MAJOR	*
*		#

01 00 2 (00)F22.3

AUTO SECTION FAULT LOC- 7SB OF MABC CAUSES > INSTEAD OF =

INDICATORS \_\_\_\_\_DISPLAY\_\_\_\_\_\_\_REPLACE ASSEMBLIES \_\_\_\_\_

FIRST ADDR 01

- (「「ずはた」だなす」です。「」」「「」」」」」」」」」」」」」」」」」」」」」」」」」」」」」」	
IESI_SET_EAULI_12100000000011A1A1A(11,14,21,22,23)	1
ITEST_SET_EAULT_1_100000000011A1A1A111,12,13.14.15.181	1
IND_GD	
NONE BLANK12A1A2A(9.11.17)	

PUNCH TAPE LEADER 12 INCHES LONG BRANCH TO ADDRESS LOCATION IN A REGISTER

01 01 2 (00)F1.10

AUTO SECTION FAULT LOC- ATWAYS START BRANCH IN STATE 2 OR BSB OF BRANCH ADDR FIELD INACTIVE- ALSO MANUAL SECTION TEST ENABLE VERTICAL PARITY CHECK PUNCH TAPE CODES - 78 78 &C. INVALID INST = 2/1/0 DOT

NO_1_LEV	ION   TEST/FAULT ELNUMBER	SELF-TEST PROGRAM	I REMARKS
		I INDICATORS I DISPLAY I BEPLACE ASSEMBLIES I LEST SET FAULT I 4000004012A1A2A(8,9,10,11)	1
1022	(02)F3C.1	AUTO SECTION FAULT LOCATION- 3SB OF MAJOR ADDR FIELD TO MABC INACTIVE- ALSO MANUAL SECTION TEST ENABLE VERTICAL PARITY CHECK PUNCH TAPE CODES - /9 /8 &C IINDIGATORSI_DISPLAYIREPLACE_ASSEMBLIES ITEST_SET_EAULT_I4000004011A1A14(21,22,23)	
1 03		PUNCH TAPE CODES - 14 18 &C	INVALID INST = 2/1/2 DCT
1 04		PUNCH TAPE CODES - 18 /8 &C	INVALID INST = 2/1/3 OCT
1 05		PUNCH TAPE CODES - /C /8 &C	INVALID INST = 2/1/4 DCT
1062	(00)F22.2	AUTO SECTION FAULT LOC- CAN NOT BRANCH OVER MAJORS- ALSO MANUAL SECTION TEST ENABLE VERTICAL PARITY CHECK PUNCH TAPE CODES - /D /8 &C IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES ITEST_SET_EAULT_I4000004011A1A14(11.14,21.23)	INVALID INST = 2/1/5 OCT
1 67		PUNCH TAPE CODES - /F /8 &C	INVALID INST = 2/1/7 OCT
C8		PUNCH TAPE CODES - 16 18 &C	INVALID INST = 2/0/6 DCT
1 09		PUNCH TAPE CODES - 16 19 80	INVALID INST = 2/2/6 OCT
1 10		PUNCH TAPE CADES - /E /9 &C	INVALID INST = 2/3/6 DCT
1 11		PUNCH TAPE CODES - 16 10 80	INVALID INST = 3/0/6 OCT
1 12		PUNCH TAPE CODES - $IE IC \&C$	INVALID INST = 3/1/6 OCT
1 13 2	(00)F14-2	AUTO SECTION FAULT LOCH OPEN INPUT TO "MTC > A"- ALSD MANUAL SECTION TES	r

TESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
	ENABLE VERTICAL PARITY CHECK PUNCH TAPE CODES - 76 70 &C IINDICATORS1_DISPLAY1BEPLACE_ASSEMBLIES ITEST_SET_FAULT_14000000012A1A2A19,101	INVALID INST = 3/2/6 UC?
01 14	PUNCH TAPE CODES - ZE ZD &C	INVALID INST = 3/3/6 OCT
01 15	PUNCH TAPE CODES - $767E$ &C	INVALID INST = 3/4/6 001
01 15 2 (00)F18.2	AUTO SECTION FAULT LOC- OPEN INPUT TO "CPJ215"- ALSO MANUAL SECTION TEST ENABLE VERTICAL PARTLY CHECK PUNCH TAPE CODES - /E /E &C (	INVALID INST = 3/5/6 DOT
C1 17	PUNCH TAPE CODES - 16 /F &C	INVALID INST = 3/6/6 OCT
01 18	PUNCH TAPE CODES - $IE IF & C$	INVALID INST = 3/7/6 OCT
01 19	PUNCH TAPE CODES - $19 / 0 \delta C$	INVALID INST = 0/1/1 OCT
01 20	PUNCH TAPE CODES - /D /O &C	INVALID INST = 0/1/5 OCT
01 21	PUNCH TAPE CODES ~ /0 /2 &C	INVALID INST = 0/4/0 OCT
01 22	DEFINE SELF VEST TAPE ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
01 23 2 (00)F19.2	AUTO SECTION FAULT LOC- OPEN INPUT TO "CPJ225"- ALSO MANUAL SECTION TEST ENABLE VERTICAL PARITY CHECK ENABLE MODE SWITCH TEST STOP TAPE	

TESTICECISION   TEST/FAULT		REMARKS
	IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIES INDNEI_8889008888124142411	1
	BRANCH TO MAJOR 01 MINOR 24 Stop Tape, Display C register, NO-GO Light ON	
01 24	STOP TAPE BRANCH TO MAJOR OI MINOR 25 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
01 25	STOP TAPE	
01 26	SET INHIBIT INCREMENT OF FLAG & ENABLE SELF TEST NOU CLOOK MODE (GTC003*) ENABLE LOW LEVEL ON GTC001*	AVOID ENABLE OF S.T. POSELX TEST DURING LOAD DE S.T. REG
	PUNCH TAPE CODES - 13 14 #0 #0 #0 #0 #0 #0 #0 #0 #0 #0 &C	SHOULD CAUSE SELF TEST REG Error
01 27	PUNCH TAPE CODES         73         74         #1	TST3 (1022 ONES) SHOULD CAUSE PROCEED ERROR

ITESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	REMARKS
I MU-ILEVELINUMBER	$ \begin{array}{c} \begin{array}{c} \begin{array}{c} \begin{array}{c} \begin{array}{c} \begin{array}{c} \begin{array}{c} \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\$	
	INITIATE SELF TEST MODE 3-COMPARE SELF TEST REGISTER TO A REGISTER WITH REPEAT PATTERN: 5	SHOULD NOT CAUSE SELF TEST REG ERROR
	INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF4FFF Branch to major of Minor 28 on ND-Go Stop Tape, Display C register, NO-GO light on	SIM NO-GO
01 28	STOP TAPE BRANCH TO MAJOR 01 MINOR 35 ON NO-GO	

ITESTIDECISION   TEST/FAULT  _NO.]_LEVEL_LNUMBER		REMARKS
01 29	RESET INHIBIT INCREMENT OF FLAG & ENABLE SELF TEST CIU CLOCK MODÉ (GTC003*) (CINCO3*)	
01 30	STOP TAPE SET INHIBIT INCREMENT OF FLAG & ENABLE SELF TEST NOU CLOCK MODE (GTC003*) DEFINE CTU TEST TAPE	
01 31 2 (00)F17.2	AUTO SECTION FAULT LOCH OPEN INPUT TO "MTC>A"- ALSO MANUAL SECTION TEST DEFINE NOU TEST TAPE	
	I INDIÇAIG3S I DI SPLAY I BEPLACE ASSEMBLIES ISELE IESI ELASHI BLANK IZAIAZA(9.11)	
	DEFINE SELF TEST TAPE SET INHISIT INCREMENT OF FLAG & ENABLE SELF TEST NOJ CLOCK MODE	
	(GTC003*) ENABLE LOW LEVEL ON GTC001*	AVOID ENABLE OF S.T. POSEIN TEST DURING LOAD OF S.T. REG
G1 Oi	BRANCH TO MAJOR 01 MINOR 1 PUNCH TAPE CODES ~ /F /7 80	MINOR 1 IF POR IN MIN 31, OTHERWISE MINOR 32
61 62		MINOR 33 IF NO POR IN MIN 31
	LOAD & RECISTER WITH A12	SET BRANCH ADOR FOR MAJ 1 Variable branch
01 00	GENERATE NO OPERATION CODE OCTAL 016 PUNCH TAPE LEAPER 12 INCHES LONG	19 800A CMS
02 00		3RD ADDR 01
	DEFINE SELF TEST TAPE Set inhibit increment of flag & enable self test nou clock mode (stcoo3*)	
	ENABLE LOW LEVEL ON GICODI*	AVDID ENABLE OF S.I. POSITE TEST DURING LOAD OF S.I. Reg
	PUNCH TAPE LEADER 12 INCHES LONG	
01 <b>61</b>	BRANCH TO ADDRISS LOCATION IN A REGISTER	VARTABLE BRANCH, MAJ 1

TESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS	
		IF = ROM	38 16
		1) FIRSE ADDR 01 2) ENC OF MAJ 01	
01 02	SPARE		
01 02 01 03 01 04	SPARE SPARE		
01 05	SPARE		
01 06 01 07	SPARE SPARE		
01 08 01 09	SPARE SPARE		
01 10	SPARE		
01 11	SP AR E		
01 12	SERIALLY LOAD THE B REGISTER WITH A4		
	INITIATE SELF FEST MODE 1-LOAD SELF TEST REGISTER WITH DEBEFFOREF PUNCH TAPE CODES - 73 71 #1 &C	INACTIVE BIT PATTE BRMJ (OPD=1+, ADDR =14	
C1 13	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON		
01 14	SERIALLY LOAD THE B REGISTER WITH A1 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFF2FFF PUNCH TAPE CODFS - /3 /1 #3 &C	SIM NCU POR BRMJ (OPD=3), ADDR =30 IF POR WORKED NOT	
01 15	MINOR OI WITH POR IN MINOR 14		
01 16	SPARE		
01 17	SPARE		
01 18		BRANCH HERE FROM V	ARIABLE
	BRANCH TO MAJOR 01 MINOR 40	BRANCH	
01 19	STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT DN		
01 20	S <sup>P</sup> ARE		
01 21 01 22	SP ARE SP ARE		

		I TEST/FAULT	I SELF-TEST PROGRAM	REMARKS
01 23			SPARE	
01 24			SP ARE	
01 25			SP AR E	
01 26			S 2 ARE	
01 27 01 28			SPARE SPARE	
C1 29			SP ARE	
01 30			SPARE	
01 31			STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	MIN 17 WITH POR IN MIN 14
01 32			SP AR E	
01 33			STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON	
01 34	2	(00)T11.2	AUTO SECTION TEST LOC- TEST IF "MTC=A" ENABLES STATE 2. USE C->ROM TO VARY BRANCH ADDR. 1ST TIME THROUGH TEST =34, 2ND TIME =30 COMPARE THE B REGISTER TO THE A REGISTER	
			LOGICALLY "AND" C REGISTER AND 03F - RESULT IN B & C REGISTER INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF0BFF BRANCH TO MAJOR 01 MINOR 4	C -> R OM
01 35			STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON	
01 36			SPARE	
01 37	2	(00)F16-2	AUTO SECTION FAULT LOC- OPEN INPUT TO "CPJ215" STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
			IINDICAIORSI_DISPLAYIBEPLACE_ASSEMBLIES IND_GOIBLANKIZAIAZAIQ	
01 38			SPARE	
61 39			STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
01 40			BRANCH TO MAJOR O1 MINOR 88	
01 41 01 42			STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
01 42			STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
01 44			· · · · · · · · · · · · · · · · · · ·	MIN 30 WITH POR IN MIN 14
			BRANCH TO MAJOR OI MINOR 81	
01 45 01 46			STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON Stop Tape, Display C register, ND-GO Light on	

NC.I LEVEL	I LESTZFAULT	SELF-TEST PROGRAM	REMARKS
		STOP TAPE, DISPLAY C REGISTER, ND-SO LIGHT DN	
		I_INGILATORSI_DISPLAYIBEPLACE_ASSEMBLIES	
		INC_COBLANK12A1A2A10	_ {
01 48 01 49		SPARE SPARE	
JI 49		STARE	
01 50 01 51		STOP FAPE, DISPLAY C REGISTER, NO-SO LIGHT ON	
01 51 01 52		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
r1 53		SPARE	
01 54		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
CI 55		SPARE	
01 56 01 57		SPARE SPARE	
C1 58 C1 59		SPARE SPARE	
		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON           IINDICATORSOISPLAY         REPLACE_ASSEMBLIES           NO_GO         BLANKIATATA(23,2)           I         I           I         I	1
01 61		SPARE	
<b>01</b> 62 C1 63		SPARE SPARE	
01 64		SP ARL	
01 65 2	(00)F21.2	AUTO SECTION FAULT LOC- OPEN INPUT 10 "CPJ225" STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHE ON	
		I INDICATORS I DISPLAY I BEANK IZALAZAII	
01 66 01 67		BEGIN TEST OF "VERIFY ENTIRE TAPE" MENORS 65-90 INITIATE SEEN TOST MODE ZELDAD SEEP TEST REGISTER WITH DESEBEORE ENABLE HI SPEED MEMORY MODE WITH ADDRESS: O DATA: O	EN LOAP OF BRED ON EMAIN
		IMITIATE SELF TEST MODE 2-LOAD SHEP TEST RESISTER WITH DESEBEOFF ENABLE HI SPEED MEMORY MODE WITH ADDRESS: O DATA:	EN LOAF DE SREG ON KMAIH

ITESTICECISION   TEST/FAULT		REMARKS
	COMPARE THE B REGISTER TO A LUGICALLY 'AND' C REGISTER AND A00008 - RESULT IN B & C REGISTER BRANCH TO MAJOR 01 MINOR 68 ON NO-GO BRANCH TO MAJOR 01 MINOR 69	
01 68	STOP TAPE, DISPLAY C REGISTER, NO-SO LIGHT ON	
01 69 01 70	INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFDFFF0FFF Compare the B register to A00008 Logically 'AND' C register and a register-result in B S C registers Branch to Major 01 Minor 71 on NO-GO Branch to Major 01 Minor 72	
01 71	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
01 72 01 73	INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF1F070FFF ENABLE HI SPEED MEMORY MODE WITH ADDRESS: 0 DATA: 0 PUNCH TAPE LEAPER 12 INCHES LONG RESET MEMORY FILL MODE PUNCH TAPE LEADER 12 INCHES LONG COMPARE THE 8 REGISTER TO A001 LOGICALLY 'AND' C REGISTER AND AE014 - RESULT IN B & C REGISTER BRANCH TO MAJOP 01 MINOR 76	EN MTW1->BREG ON KMVOII
01 74	STUP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
01 75 2 (00)710.1	AUTO SECTION TEST LOCATION- NO STATE 2 WITH UNBR, CHECK STATE 2 WITH BRMJ BRANCH TO MAJOR 01 MINOR 60	
01 76 01 77	INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OF9FFFOFFF Compare the B register to aeo14 Logically 'And' c register and a register-result in B & C registers Branch to major of minor 78 on NO-Go Branch to major of minor 79	

TESTIDECISION   TEST/FAULT	I SELF-TEST PROGRAM	1 REMARKS
01 78	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
01 79 01 80	LUAD A REGISTER WITH 012	
	ENABLE MEMORY VERIFY ENTIRE TAPE MODE STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
01 81	SPARE	
61 82	SP ARE	
01 83 01 84	SPARE SPARE	
01 85	SPARE	
C1 86	SPARE	
01 87	SPARE	
01 88	SPARE	
01 89	SPARE	
C1 90	SP AR E	
01 91	SPARE	
01 92	SPARE	
01 93	SPARE	
01 94	SP AR E	
01 95 01 96	SPARE SPARE	
01 97	SPARE	
01 98	SPARE	
61 99	MINOR 85 TF POR IN MINOR 14 Load a register with 01800	SET UP BRANCH ADDR FOR
		VARIABLE BRANCH MAJ 1 MIN 1
	FOLLOWING IS 498 NO DPS PUNCH TAPE CODES - /E /O &C /E	
	/0 &C /E /0	
	23 0/ H/ D3	
	/0 &C /E /0	
	33     0     3     0     3     0     3     0     3     0	
	/E /O &C /E	
	/0 & 2 / 23 0/ = / 23 0/ = / 23 0/ = / 23 0/ E / 23 0/	
	<b>33 C/ 3/ 33 O/ 3/ 33 O/ 3/ 33 O/ 3/ 33 O/ 3/ 33</b>	
	/E /O 23 0/ E/	
	0 A A D A A D A A D A D A D A D A D A D	
	30 /E /O 30	
	/E /O &C /E	
	0	
	ΛΕ /Ο ΔΕ /Ε	
	/0 SC /E /0 &C /E /0	
	30 / E / D 30 / D 30 / E / D 30 /	

ESTIDECISION   TEST/FAULT   NG.1_LEVELNUMBER	SELF-TEST PROGRAM	REMARKS
	A 23 01 A	
	/0 SC /E /0	
	23 0/ E/ 23 0/ E/ 25 0/ E/ 23 0/ E/ 23 0/ E/ 23 0/ E/ /E/ 23 0/ E/	
	/0 &C /E /0	
	22 O/ E/ 23	
	/E /O &C /E	
	0 = 1 33 0 = 23 0 = 23 0 = 23 0 = 23 0 = 23 0 = 23 0	
	SC /E /O SC	
	/E /O &C /E /O &C /E /O &C /E /O &C /E /O &C /E /O	
	0 de /e /0	
	/E /O &C /E	
	/0 SC /E /0	
	33 O/ 3/ 33	
	/E /O &C /E	
	/0 &C /E /0	
	33 0/ 3/ 33 0/ 3/ 33 0/ 3/ 33 0/ 3/ 33 0/ 3/ 33 0/ 3/ 3/ 32 0/ 3/ 33 0/ 3/ 33 0/ 3/ 33 0/ 3/ 33 0/ 3/	
	/0 SC /E /0	
	SC /E /O SC	
	/E /O &C /E	
	/O &C /E /O	
	23 0/ E/ 22 0/ F/ 23 0/ E/ 23 0/ E/ 23 0/ E/ 23 0/ E/ 23	
	/E /O &C /E /O &C /E /O &C /E /O &C /E	
	0/ 3/ 03 0/ 3/ 03 0/ 3/ 03 0/ 3/ 03 0/ 3/ 03 0/ 3/ 03 0/ 3/ 03 03 0/ 3/ 03 0/ 3/ 03 0/ 3/ 03 0/ 3/ 03 0/ 3/ 03 0/ 3/ 03	
	/E /O &C /E	
	/0 X X X X X X X X X X X X X X X X X X X	
	33 0/ E/ 33 0/ E/ 33 0/ E/ 38 0/ E/ 38 0/ E/ 38 0/ E/ 38	
	AV 33 0Y AV	
	0 A A C A A C A A C A A C A C A C A C A	
	D3 0/ E/	
	23 C / E / D & C / E / D & C / E / D & C / E / D & C / E / D & C / E / D	
	/E /O &C /E	
	0/ 3/ 33 0/ 3/ 33 0/ 3/ 33 0/ 3/ 38 0/ 3/ 38 0/ 3/ 32 0/	
	33 C/ E/ 33 O/ E/ 33 O/ E/ 32 O/ E/ 33 O/ E/ 33 O/ E/ 33	
	/E /0 &C /E /0 &C /E /0 &C /E /0 &C /E	
	/O &C /E /O	
	D2 0\ 3\ D3 0\ 4\ D3 0\ 4\ D2 0\ 4\ D3 0\ 4\ D3 0\ 4\ D3 0\ 4\ A D3 0\ 4\ D3 0\ 4\ D3 0\ 4\ D2 0\ 4\ D3 0\ 4\ D3 0\ 4\ D3 0\ 4\	
	/0 &C /E /0	
	23 O/ E/ 23	
	1 23 0 1 1 23 0 1 1 23 0 1 3 0 3 0 1 1 23 0 1 1 23 0 1 1 23 0 1 1	
	0/ 3/ 23 0/ 3/ 23 0/ 4/ 23 0/ 4/ 23 0/ 4/ 23 0/ 4/ 23 0/	
	23 0/ E/ 03	
	/E /O &C /E	
	0\ 3\ 2& 0\ 3\ 2& 0\ 9\ 3& 0\ 3\ 3& 0\ 3\ 2& 0\ 3\ 2& 0\ 3\ 3& 0\ 3\ 3& 0\ 3\ 3& 0\ 3\ 3& 0\ 3\ 3& 0\ 3\ 3& 0\ 3\ 3& 0\ 3\ 3& 0\ 3\ 3& 0\ 3\ 3& 0\ 3\ 3& 0\ 3\ 3& 0\ 3\ 3& 0\ 3\ 3& 0\ 3\ 3& 0\ 3\ 3& 0\ 3\ 3& 0\ 0& 0\ 3& 0\ 0& 0& 0\ 0&	
	/E /O &C /E	
	/0 4C /E /0	

TESTIDECISION   TEST/FAULT     NO.L LEVEL   NUMBER	SELF-TEST PROGRAM	
	A/ 33 0/ A/	
	0 30 74 03 01 31 00 31 01 33 01 31 03 01 31 03 01	)
	C3 C/ H/ C3	
	31 03 01 31 03 01 31 03 01 31 03 01 31 03 01 31	
	0 80 /E /O	)
	03 01 BY 03	
	72 /0 &C /E	
	0/ F/ D3 0/ F/ D3 0/ F/ D2 0/ F/ D3 0/ F/ D3 0/	)
	0.8 OV BV 08	
	A 03 01 B1	
	0/ 3/ 02 0/ 3/ 02 0/ 3/ 02 0/ 3/ 02 0/ 3/ 03 0/	)
	03 0/ 3/ 03 0/ 3/ 03 0/ 3/ 03 0/ 3/ 03 0/ 3/ 03	
	75 /0 &C /E /0 &C /E /0 &C /E /0 &S /E /0 &C /E	
	0/ 3/ 32 0/ 3/ 33 0/ 3/ 33 6/ 3/ 33 0/ 3/ 33 0/ 3/ 33 0/	
	03 01 E1 03 01 E1 03 01 E1 03 01 E1 02 01 E1 02	
	/F/0 &C/E/0 &C/E/0 &C/E/0 &C/E/0 &C/E/0 &C/E	
	0 K H 23 0 H H 23 0 K H 28 0 K H 28 0 K H 28 0 K H	
	03 0\ F\ 33 0\ F\ 33 0\ F\ 33 0\ F\ 33 0\ F\ 32 0\ 3	
	H 23 0/ H	
	DA C/ H/ DA O/ H/ DA O/ H/ DA O/ H/ DA O/ H/ DA	
END OF MA.		

We want was was well and the state of the st	Procession and an experimental and an experimental and the PART Control of			· · · · · · · · · · · · · · · · · · ·	
TERSERECTS TON FOR STRENULT OF	SELF-TES	T PROGRAM	1	REMARKS	i i
I MO.I LEVEL I MUMBER !					1

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5		4
*	MAJOR TEST 02	¥
*		*
*		*
*	CONTAINS THE FOLLOWING SECTIONS :	*
*	1)TEST T30 OF AUTO SECTION	*
*	2) TEST (00) T1.11.3 UF AUFO SECTION	*
ales apr	3)TEST (00)T3.6.G.3 OF AUTO SECTION	*
2	4) VARIOUS AUTO SECTION FAULT LOC.	*
- 2	51BRANCH LOC TO AVOID PROCEED ERROR	*
*		*
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02 00 2

(00)F22.4

FAULT IN MABC, < INSTEAD OF = LOAD A REGISTER WITH 001 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON PUNCH TAPE LEADER 12 INCHES LONG

INDICATORS   DISPLAY   REPLACE AS	EMBLIES
ITEST SET FAULT [21000000000]1A1A1A(23.14)	
IIAIA2A15	
ND_GOixxxxxxxxxx12A1A2A(8+9+10+11)	CPJ036*
<pre>[IEST_SEL_FAULI_10000000011A1A1A121.22.23]</pre>	MPC062

FOLLOWING IS 524 NO OPS PUNCH TAPT CODES - /E /O &C /E /C &C /E /O 33 O/ E/ 08 C/ E/ 08 O/ E/ 08 O/ E/ 08 O/ E/ 08 1E 10 &C /E 01 J1 02 01 31 02 01 31 02 01 31 02 01 31 02 01 31 03 01 33 OV 31 33 OV 11 JO &C /E /O &C /E /O &C /E /O &C /E /O &C /E 01 31 33 01 31 33 01 31 33 01 31 33 01 31 33 01 31 33 01 33 OV EV 33 78 70 80 /E 01 31 03 01 31 03 01 31 03 01 31 03 01 31 03 01 23 61 31 23 61 31 23 61 31 23 61 31 23 61 31 23 61 31 23 JE 10 &C JE 70 &C /E /O 28 C/ E/ 0 &C /E /0 &C /E /0 &C /E /0 &C /E /0 &C 7E 70 &C 7E ON EVIDENCIAL D3 ON EVID & SC /E /O SC 31 33 01 31 33 01 31 33 01 31 33 01 31 33 01 31 07 BV 33 0V BV 03 0V BV 03 0V BV 03 0V BV 03 0V

TESTICECISION   TEST/FAULT   NO.L_LEVEL   NUMBER	SELF-TEST PROCRAM	! ЗЕМАЗКS
	$ \begin{array}{c} 5.5 \\ 5.6 \\ 5.7 $	/E         /0         &C         //E         /0         &C         //E         /0         &C         //E         /0         &C         //E     <

TESTIFECISION		SELF-TEST PROGRAM	I REMARKS I
2	(00)F1.12 (00)F3.8 (00)F3.8 (00)F9.4 (00)F9.4	ND BRANCH OR T. S. CONTROL          80       A.S. CHE /0       SC /E /0	
02 01 2	(00)F1.1	AUTO SECTION FAULT LOC - BRANCH WITHIN MAJ INACTIVE ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT DN IINDICATORSL_DISPLAYL	1
02 02 02 03		SPARE SPARE	
02 04 3	(00)73.6.7	AUTO SECTION BRANCH LOC- TRANS T3.6.N -> T3.6.NN THRU MAJ 2 TO AVGID PROCEED ERROR AT 02 00 BRANCH TO MAJOR 19 MINOR 3	GJ TO T3.6.NN

TFSTIC	CECISION	I TESTZEAULT INUMPER	SELF-TEST PROGRAM	REMARKS
02 05	5	(00)F3.6.G	FAULT IN WALF FOR END OF DATA STOP TAPF, DISPLAY C REGISTER, NO-GO LIGHI ON IINDICATORSI.DISPLAYI	APF351≉ 591
02 06	1	011	AUTO SECTION TEST LOCATION - TEST OF LS8, 658, 458, 358 OF MABC PREVIOUS TEST = (00)T22 ENABLE VERTICAL PARITY CHECK BRANCH TO MAJO? 37 MINOR 2	
02 <b>07</b>	2	(00)F3.5	INPUT TO "BRANCH WITHIN MAJ" OPEN ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I <u>INDICATORS L DISPLAY</u> <u>EPLACE ASSEMBLIES</u> IND GO	
02 08 02 09			SP <b>A</b> RE SPARE	
02 10	1		MANUAL SECTION BRANCH LOCH FRANSFER OD 12 -> 12 01 THRU HERE TO AVUID PROCEED ERROR AT 02 00 BRANCH TO MAJOR 12 MINOR 1	CO TO FINAL TESTS OF MARMAN Memory Control Trests
02 11 02 12 02 13 02 14 02 15 02 16 02 17 02 18			SP AR F SP AR E SP AR E SP AR E SP AR E SP AR E SP AR E SP AR E	
02 <b>19</b> 02 20	3	(00)71.11.	TEST SCU INST RECODE MATRIX USING LPAB & CMAB Serially Luad the B register with AAAAAAAA Compare the R register to 55555555 Branch to Major of Minor 21 on ND-50	
	L <sub>é</sub> .	F1.11.2.6	FAULT IN SCU INST DECODE MATRIX, LSOD=3 ENABLE VERTICAL PARITY CHECK PUNCH TAPE CODES - 78 /8 &C STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	INVALID INST = 27173 DOTAL

		TEST/FAULT  NUMBER	I SELF-TEST PROGRAM	I REMARKS
			IINDICAIGRSI_DISPLAYIBEPLACE_ASSEMBLIES IIESI_SET_EAULI_I4000000012A1A2A11.2) IIESI_SEI_EAULI_I400000401HIGHER_LEVEL_DE_MAINIENANCE IND_GOIBLANKIPROCEED_PER_PARAGRAPH_13=3	IAI544 SDO   IAI544 STRING
02 21 4	÷	F1.11.2.N	FAULT AT BRMJ IBT OR LATCH ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYI	t 1
D <b>2 22</b> 5	5	(00)F3.6.G	FAULT IN NO-GO "OR"GATE ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINCIGATORS1_DISPLAY_1BEPLACE_ASSEMBLIES IND_GO1_170000000012A1A2A06	
02 23 02 24 02 25 02 26 02 27 02 28 02 29			SP ARE SP ARE SP ARE SP ARE SP ARE SP ARE SP ARE	
230 3	3	(01)F11.2.	"MTC= A" OK BUT "MTC>A" FAILS ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICAIOBSI_DISPLAYI	
02 31 02 32 02 33			SP ARE SP ARE SP ARE	
02 34 3	3	(01)F11.2.	BOTH "MTC>A" & "MTC=A" FAIL ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	

		***************************************
TESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	REMARKS
I_NO.I_LEVEL_INUMBERI		

		INDICATORS I DISPLAY I REPLACE ASSEMBLIES	.1
		IND_GQ1_3200000012A1A2A(8:10)	_  CFJ036* Sal
02 35	SP AR F		
02 36	SPARE		
02 37	SPARE		
02 38	SPARE		
02 39	SPARE		
02 40	SPARE		
02 40	SPARE		
02 41	SPARE		
02 42	SPARE		
02 44	SPARE		
02 45	SPARE		
02 46	SPARE		
02 47	SP AP E		
02 48	SPARE		
02 49	SPARE		
C2 50	SPARE		
02 51	SP AR E		
02 52	SPARE		
02 53	SPARE		
02 54	SPARE		
02 55	SPARE		
02 56	SPARE		
02 57	SPARE		
02 58	SPARE		
02 59	SP AR E		

02 60 3 (01)F10.1. CAN NOT BRANCH IN REV DIRECTION, NO AUTO START T.S. ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-SO LIGHT ON

INDICATORS	1_DISPLAY	I REPLACE ASSEMBLIES	
IND GO	I BLANK	114141410	
1	1	14143405	
I		12 41 42 4 (11 + 8 + 9 + 17)	

0.2	61	SPARE
02	62	SP AR E
02	63	SPARE
62	64	SPARE
02	65	SPARE
02	66	S <sup>D</sup> AR E
02	67	SPARE
02	68	SPARE
02	69	SPARE
C 2	70	SP AR E
02	71	S⊇ AR E

		I TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
2 72 2 73			SPARE SPARE	
274 275	4	(0C)T3.6.G	TEST SCU INST DECODE MATIX USING ISI1 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBEFFOFF7 COMPARE THE & REGISTER TO A BRANCE TO MAJO? 2 MINOR 76 ON NO-GO	PJB -> RIM
	5	F3.6.G.3.0	FAULT IN SCU INST DECODE MATRIX, LSDD=5 ENABLE VERTICAL PARITY CHECK PUNCH TAPE CODES - /D /8 &C STOP TAPE, DISPLAY C REGISTER, ND-GD LIGHF ON	INVALID INSR = 2/1/5 DOTA
			INDICATOPSIDISPLAY.I.REPLACE ASSEMBLIESI IEST SET FAULT.I.4000000124142411,21 IEST SET LAULI I.400000401HIGHER LEVEL DE MAINTENANCEI INO.GOI.BLANK.IPBOCEED PER PARAGRAPH.13=3I	LAI546 STRING
276	5	F3.6.3.3.N	HNMJ IBT OF LATCH ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATOPSL_DISPLAYLREPLACE ASSEMBLIES INO_GOL_TTTTTTTTTTL2A1A2A(1:6)	
2 77 2 78 2 79			SPARE SPARE SPARE	
80 81 82 83			SP ARE SP ARE SP ARE SP ARE	
2 84 2 85 2 86 2 87			SPARE SPARE SPARE SPARE	
2 88 2 89 2 90 2 91			SPARE SPARE SPARE SPARE	
2 92 2 93 2 94 2 95 2 95			SPARE SPARE SPARE SPARE	
296 297 298			SPARE SPARE SPARE	
299			END OF MAJOR TEST	

TESTIDECISION   TESTING	•	SELF-TEST PROGRAM	I REMARKS
04 00	PUNCH TAPE LE	AFER 12 INCHES LONG	
	DEFINE SELF T	EST TAPE	
	SET INHIBIT I	NOREMENT OP FLAG & ENABLE SELF TEST NOU CLOCK MODE	E
	(GTC003#)		
	ENABLE LOW LE	VEL ON GTCOO1≄	
	BRANCH TO MAJI	OR 5 MINOR O	
	STOP TAPE, DI	SPLAY C REGISTER, NO-GO LIGHT ON	
04 01	BRANCH TO MAJ	OR 5 MINOR 2	
	STOP TAPE, DI	SPLAY C REGISTER, NO-GO LIGHT ON	
04 02	BRANCH TO MAJ	DR 5 MINOR 3	
	STOP TAPE, DI	SPLAY C REGISTER, NO-GO LIGHT ON	
04 03		OR 5 MINOR 4 ON NO-GO	
		SPLAY C REGISTER, NO-GO LIGHT ON	
04 04	END OF MAJOR		

ITEST[PECISION   TEST/FAULT   I_NO_1LEVELNUMBERL	SELF-TEST PROGRAM	REMARKS	
05 00	STOP TAPE		
	BRANCH TO MAJOP OS MINOR 5		
	STOP TAPE, DISPLAY C REGISTER, NO-GD LIGHT ON		
05 01	STOP_FAPE		
	BRANCH TO MAJUR 4 MINOR 1		
	STOP TAPE, DISCLAY C REGISTER, NO-GO LIGHT ON		
05 02	STOP TAPE		
	INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF4FFF	SIM NO-3D	
	BRANCH TO MAJOP 4 MINOR 2 ON NO-SO		
	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON		
05 03	STOP TAPE		
	INITIATE SELF LEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF4FFF	SIM NO-GO	
	BRANCH TO MAJOR 4 MINOR 3		
	STOP TAPE, DISPLAY C REGISTER, ND-GD LIGHT ON		
05 04	STOP TAPE		
	BRANCH TO MAJOR 05 MINOR 6		
	STOP TAPE, PISPLAY C REGISTER, ND-GO LIGHT ON		
05 05	BRANCH TO MAJOR 05 MINOR 1		
	STOP TAPE, DISPLAY C REGISTER, NO-SO LIGHT ON		
05 06	ENABLE VERTICAL PARITY CHECK		
05 07	END OF MAJOR TEST		

TESTIDECISIO	ON   TEST/FAULT LLNUMBER	SELF-TES	T PROGRAM	I REMARKS
	**************************************	**********	*********	* * * * * * * * * * * * * * * * * * *
	*	TEST FORMAT CHECK	WITH WRUNG FORMAT	*
	* *******	********	*****	* * * * * * * * * * * * * * * * * * * *
06 00		DEFINE SELF TEST TAPE 1ST ADDR CHAR FOLLOWING 2ND INST CHA PUNCH TAPE CODES - /F /7 @6	R	ADDR = 50 01
		PUNCH TAPE CUDES - DO /F /7 &C /F	/7 &C	SET UP TEST ADDR
		IST ADDR CHAR FULLOWING IST INST CHA PUNCH TAPE CODES - /F 26	R	ADDR = 50 02
		2ND INST CHAR FOLLOWING IST ADDR CHA PUNCH FAPE CODES - 77	R	ADDR = 60 03
		2ND ADDR CHAR FOLLOWING 2ND INST CHAP PUNCH TAPE CODES - 20	R	ADDR = 06 00
		PUNCH TAPE CODES - /F /7 &C /F /7	εC /F /7 εC /F /7 εC	SET UP TEST ADDR
		IST INST CHAR FOLLOWING DATA CHAR PUNCH TAPE CODES - #C /F		ADDR = 06 04
		PUNCH TAPE CODES - /7 &C		SET UP TEST ADOR
		1ST INST CHAR FOLLOWING 1ST ADDR CHA PUNCH TAPE CODES - 06 /F	R	ADUR = 60 05
		2ND ADDR CHAR FOLLOWING 1ST INST CHA PUNCH TAPE CODES - 20	R	ADDR = 06 00
		PUNCH TAPE CODES - /F /7 &C /F /7 PUNCH TAPE CODES - /F /7 &C /F /7		SET UP TEST ADDR
		DATA CHAR FOLLOWING IST INST CHAR PUNCH TAPE CODES - /F #G		ADDR = 06 06
		2ND INST CHAR FOLLOWING DATA CHAR PUNCH TAPE CODES - 77		ADD3 = 06 07

ITESTIDECISION   TEST/FAULT		I REMARKS
	PUNCH TAPE CODES - &C /F /7 &C	SET UP TEST ADDR
	DATA CHAR FOLLOWING IST ADDR CHAR PUNCH TAPE CODES - 26 #6	ADDR = 60 08
	2ND ADDR CHAR FOLLOWING DATA CHAR PUNCH TAPE CODES - 20	ADDR = 05 00
	PUNCH TAPE CODES - /F /7 &C /F /7 &C /F /7 &C Punch Tape Codes - /F /7 &C /F /7 &C /F /7 &C Punch tape codes - /F /7 &C /F /7 &C /F /7 &C	SET UP TEST ADDR
	END OF DATA CHAR FOLLOWING 1ST ADDR CHAR Punch tape codes - 26 80	ADDR = 60 09
	PUNCH FAPE CODES - @0 /F /7 &C PUNCH TAPE CODES - /F /7 &C /F /7 &C /F /7 &C PUNCH TAPE CODES - /F /7 &C /F /7 &C /F /7 &C PUNCH TAPE CODES - /F /7 &C /F /7 &C /F /7 &C	SET UP TEST ADUR
06 10	7 HOLE PRESENT PUNCH TAPE CODES - 40	
06 11	HORIZONTAL PARITY EVEN => FAULT PLNCH TAPE CODES - 84 PUNCH TAPE CODES - 88 08 80	2ND & 3RD CHAR EVEN VERTIC
	CHECK FOR CORRECT VERTICAL PARITY PUNCH TAPE CODES - /1 /5 &9	PARITY Enable Vertical Parity Che
06 12	COLUMN 1 = ODD VERTICAL PARITY => FAULT PUNCH TAPE CODES - &4 PUNCH TAPE CODES - /1 /5 &5	ENABLE VERTICAL PARITY CHE
06 13	COLUMN 2 = ODD VERTICAL PARITY PUNCH TAPE CODES - £4 PUNCH TAPE CODES - 02 PUNCH TAPE CODES - /1 /5 £5	SET UP VERTICAL PARITY FAU Enable vertical parity che
06 14	COLUMN 3 = ODD VERTICAL PARITY PUNCH TAPE CODES - 84 PUNCH TAPE CODES - 02	SET OF VERTICAL PARITY FAD

TESTIDECISION   TEST/FA		SELF-TEST PROCRAM	P.EMARKS
	PUNCH TAPE CODE	S - /1 /5 80	ENABLE VERTICAL PARITY CHECK
06 15	COLUMN 4 = ODD VE PUNCH TAPE CODE PUNCH TAPE CODE PUNCH TAPE CODE	s - ε4 s - 08	SET UP VERTICAL PAPITY FAULT FNABLE VERTICAL PARITY CHECK
06-16	COLUMN 6 = ODD VF PUNCH TAPE CODT PUNCH TAPE CODT PUNCH TAPE CODT	S - δ4 S - 20 80 80	SET UP VERTICAL PARITY FAUL Enable Vertical Parity CHEC)
96 17	COLUMN 8 = ODD V PUNCH TAPE COD PUNCH TAPE COD PUNCH TAPE COD	$S = \frac{54}{5} = \frac{20}{20} = \frac{80}{80} = \frac{80}{80}$	SET UP VERTICAL PARITY HAUL ENABLE VERTICAL PAPITY CHEC
06 i8	CHECK FOR CORREC PUNCH TAPE CODI PUNCH TAPE CODI	- £4	CLEAR VERTICAL PARITY ENABLE VERTICAL PARITY CHEC
	END OF MAJOR T	ST	

	TESTZFAULT		REMARKS
	, و به به به به به الله عن الله عن الله عن الله الله الله الله الله الله الله عن الله الله الله الله الله الله	······································	
		**************************************	******
*		IN-PROCESS REGISTER FAULTS TESTS AND REGISTERS TESTS	*
**		***************************************	*
07 60		DEFINE SELF TEST TAPE SET INHIBIT INCREMENT OF FLAG & ENABLE SELF TEST NOU CLOCK MODE (STC003*)	
		ENABLE LOW LEVEL ON GTCOOL*	
		COMPARE THE B PESISTER TO 0000000	BOTH ASB REG SATURATED WITH O S => NO FAULT
01		COMPARE THE B REGISTER TO FFFFFFF	A ALL 1 S, B ALL O S ≠> FAULT
02		INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF8FDF0F8F SFRIALLY LOAD THE B REGISTER WITH FFFFFFF COMPARE THE B REGISTER TO 00000000	SREG->DSPL, MSHD DSPL->RIM
07 03		INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFDF0FBF SERIALLY LOAD THE B REGISTER WITH AFFFFFFF	A ALL O S,B ALL 1 S => FAUL GREG->DSPL, MSHD DSPL->RIM
07 04		COMPARE THE B REGESTER TO O INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBEDFOFBE LOGICALLY "AND" C REGISTER AND AFFFFFFF - RESULT IN B & C REGISTER	TEST OL AREG GREG->DSPL, MSHD DSPL->RIN TEST C->B & PE OF MSHD WITH
		COMPARE THE B REGISTER TO THE A REGISTER	AANC BREG SATURATED WITH 1 S => FAULT
07 05		INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFORBF LOGICALLY 'AND' C REGISTER AND AFFFFFFF - RESULT IN B & C REGISTER	MSHO DSPL=0->RIM TEST C=0 S->B & PE OF MSHO WITH AANC
		COMPARE THE B REGISTER TO A	BREG SATURATED WITH 0 S => FAULT
06		LOGICALLY "AND" C REGISTER AND AFFFFFFF - RESULT IN B & C REGISTER COMPARE THE B REGISTER TO 5 ENABLE VERTICAL PARITY CHECK	
07 07		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHE ON SERIALLY LOAD THE B REGISTER WITH AFFFFFFF COMPARE THE B REGISTER TO A	
08 08		SFOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBEDFOEBF SERIALLY LOAD THE B REGISTER WITH FEFTERET	GREG->DSPL, MSHD=F->R1M
		COMPARE THE B REGISTER TO THE A REGISTER	BOTH AKB REG SATURATED WITH 15 =>NO FAULT
09		SERIALLY LOAD THE B REGISTER WITH AFFIFEF COMPARE THE P PERISTER TO THE A REGISTER BRANCH TO MAJOR OF MINOR TO ON NO-SO BRANCH TO MAJOR 07 MINOR TI	
07 10 7 11		STOP FAPE, DISPLAY C REGISTER, ND-GO LIGHT ON	
7 12		LOGICALLY "AND" C REGISTER AND AFFFFFFF - RESULT IN G & C REGISTER COMPAKE THE 3 PEGISTER TO A BRANCE TO MAJUP OF MINOR 13 ON NO-CO	

TESTIDECISION   TEST/FAULT	SELF~TEST PROGRAM	REMARKS
	BRANCH TO MAJOP 97 MINOR 14	
07 13	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
07 14		
07 15	SERIALLY LOAD THE B REGISTER WITH AFFFFFF	
	COMPARE THE B BEGISTER TO THE A REGISTER	
	BRANCH TO MAJOR 07 MINOR 16 ON ND-30	
	BRANCH TO MAJOR 07 MINOR 17	
07 16	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
07 17	Star TAREY BIS EAT & REDISTERY AD BU CIONT ON	
07 18	SERIALLY LOAD THE B REGISTER WITH A0000000	
01 10	COMPARE THE B REGISTER TO THE A REGISTER	
	BRANCH TO MAJOR C7 MINOR 19 ON ND-GO	
	BRANCH TO MAJOR OF MINOR 20	
07 19	STOP TAPE, DISPLAY C RECISTER, NO-GO LIGHT ON	
07 20	STOP TAPE, DISPLAT & REDISTER, NU-BU LIGHT ON	
07 21	SERIALLY LOAD THE B REGISTER WITH AFFFFFF	
07 21	SERIALLY LOAD THE B REGISTER WITH AFFFFFFF	
	COMPARE THE & REGISTER TO A0000000	
	BRANCH TO MAJOF 07 MINOR 22 ON NO-GO	
07 22	BRANCH TO MAJOR 07 MINOR 23	
07 23	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
07 24	SERIALLY LOAD THE B REGISTER WITH AFFFFFF	
	COMPARE THE B REGISTER TO AEFFFFF	
07 06	BRANCH TO MAJOR 07 MINOR 26 ON NO-GO	
07 25	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
07 26		
07 27	LOGICALLY 'AND' C REGISTER AND AFFFFFF - RESULT IN B & C REGISTER	
	COMPARE THE B REGISTER TO A	
	BRANCH TO MAJO® 07 MINGR 29 DN ND-GO	
07 28	STOP TAPE, DISPLAY C REGISTER, ND-G0 LIGHT DN	
07 29		
07 30	COMPARE THE B REGISTER TO A1	
	BRANCH TO MAJOP OF MINOR 31 ON NO-GO	
	BRANCH TO MAJOR 07 MINOR 32	
07 31	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
07 32	ENABLE VERTICAL PARTTY CHECK	
07 33	END OF MAJOR TEST	

FIDECISION   TEST/FAULT   EVELLNUMBERL	SELF-TEST PROGRAM	REMARKS
<u>t</u>		
****	******	*****
*		*
*	MANUAL MEMORY TEST CONTROL SELF TEST	*
*	MAJORS 8, AND 10 - 12	*
* **	*******	* *******
o	DEFINE SELF TEST TAPE	
	SET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST NOU CLOCK MODE (GTC003*)	
	ENABLE LOW LEVEL ON GTCOOI*	
1	ENABLE LO SPEED MEMORY MODE WITH ADDRESS: O DATA:	
	PUNCH TAPE LEADER 24 INCHES LONG	
	RESET MEMORY FILL MODE	
	STOP TAPE	
2	ENABLE HI SPEED MEMORY MODE WITH ADDRESS: O DATA:	
	PUNCH TAPE LEADER 36 INCHES LONG	
	RESET MEMORY FILL MODE	
	PUNCH TAPE LEADER 12 INCHES LONG	
	STOP TAPE	
3	INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH DF7F0F0FFF	SIM CM7, INH ALL MEM
	ENABLE WORST CASE MEMORY MODE-ADDRESS: O PATTERN: O	
4	RESET MEMORY FILL MODE	
5	ENABLE VERTICAL PARITY CHECK	
6	END OF MAJOR TEST	

TESSIDEDISION	I DISTZFAULT	SELF-TEST PROGRAM	1	REMARKS	
9 00					
9 01		ENABLE VERTICAL PARTTY CHECK STOP TAPE, DISPLAY C REGISTER, NO-SO LIGHT ON			
9 02 2	F242.1 F332.1	AUTO FAULT LOC - ABSILE OR ABSILE SPO STOP LAPE, DISPLAY C REGISTER, NO-GO LIGHT ON			
		IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIES IND_GUIBLANKIIAIAIA22			
9 03		END OF MAJOR TEST			

TESTIGECTSION   TEST/FAULT     NO.L LLYEL   NUMBER	SELF-TEST PROGRAM	REMARKS
10 00	DLFINE SELF TEST TAPE SET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST NOU CLOCK MODE (GTC003*) ENABLE LOW LEVEL ON GTC001*	
10 01 10 02	ENABLE LO SPEED MEMORY MODE WITH ADORESS: O DATA: O RESET MEMORY FILL MODE	
10 03 10 04	BRANCH TO MAJOR 11 MINOR 20 END OF MAJOR TEST	

TREST DECISION   TEST/FAULY F NGLE LIVEL	SELE-TEST PROGRAM	0.5 MALK ( 5
11 80 11 41	BRANCH TO ADDRESS LOCATION IN A REGISTER ENABLE HI SPEEL MEMORY MODE WITH ADDRESS: 0 DATA: A022C680 PUNCH TAPE FEADER 12 INCHES LONG	VARIABLE BRANCH
21 - 02	STOP TAPE SERIALLY LOAD THE 8 REGISTER WITH A0180008 COMPARE THE 8 PEGISTER TO A INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH 8F3F8F0PFF ENABLE HI SPEED MEMORY MODE WITH ADDRESS: 0 DATA: A022C680 PUNCH TAPE LEAPER 12 INCHES LONG	CREG->ROM, ROM->#1 DR, LUAT BREG ON KMA152
1 03	BRANCH TO MAJOR 11 BINOR 4 ON NO-GO BRANCH TO MAJOR 11 MINUR 5	
11 04	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
11 05	LOAD A REGISTER WITH A26 RESET MENGRY FILL MODE PUNCH TAPE LEADER & INCHES LONG STOP TAPE	
11       06         11       07         11       08         11       09         11       10         11       11         11       12         11       13         11       14         11       15         11       16         11       17         11       18         11       19	SP ARE         SP ARE	
11 20	STOP FAPE PUNCH TAPE LEADER 6 INCHES LONG SERTALLY LOAD THE B REGISTER WITH ADTAC688 COMPART THE R REGISTER TO A INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH 8F3F0F08FF RESET MEMORY FILL MODE PUNCH TAPE LEADER 3 INCHES LONG	CRED>ROM, ROM->WI DR, 10) All MEM

TESTICECTSION   TEST/	FAULT ( BERL	SELF-TEST PROGRAM	I REMARKS	 
11 21	STOP TAPE, DISP	LAY C REGISTER, NO-GO LIGHT ON		
11 22 11 23 11 24 11 25	SP AR E SP AR E SP AR E SP AR E			
11 26	ENABLE VERTICAL	PARITY CHECK		

 II 27
 END OF MAJOR TEST

TESTIDECISION   TEST/FAU _NQ_1LEVEL1NUMBER	LT   SELF-TEST PROGRAM	REMARKS
2 00	DEFINE SELF TEST TAPE SET INHIBIT INCREMENT OP FLAG & ENABLE SELF TEST NOU CLOCK MODE (STO003*) ENABLE LOW LEVEL ON STO001*	AUTO MODE MEMORY VERIEY Tests
	BRANCH TO MAJO? 12 MINUR 3	
2 01	STOP TAPE	
2 02 2 03	BRANCH TO MAJOR 12 MINOR 7 LOAD A REGISTER WITH 004 ENABLE MEMORY VERIFY ENTIRE TAPE MODE	
2 04	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
2 05 2 116	SH AR E Sh Ar E	
2 07	ENABLE HI SPEED MEMORY MODE WITH ADDRESS: 0 DATA: 0 PUNCH TAPE LEADER 12 INCHES LONG RESET MEMORY FILL MODE PUNCH TAPE LEADER 12 INCHES LONG	
2 08	STOP TAPE	
2 09	ENABLE HI SPEED MEMORY MODE WITH ADDRESS: O DATA: O PUNCH TAPE LEADER 12 INCHES LONG ENABLE MEMORY VERIFY ENTIRE TAPE MODE PUNCH TAPE LEADER 3 INCHES LONG	
2 10	STOP TAPE PUNCH FAPE LEADER 12 INCHES LONG	
2 11	RESET MEMORY FILL MODE RUNCH TAPE LEADER 6 INCHES LONG	
2 12	Start	

ITESTIDECISION I TEST/FAULT I	SELF-TEST PROGRAM	REMARKS
12 13	BRANCH TO MAJOR 12 MINOR 15	
12 14	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
12 15 12 16	ENABLE VERTICAL PARITY CHECK END OF MAJOR TEST	

	NUMBER		
		-L	
	****	**************************************	<b>***********</b> *****
	*		41
	*	MANUAL MULTIPLEXER SYSTEM YESTS, MAJORS 14 & 16	*
	*	PART 1 = MAJOR 14	*
	<b>≠</b> ¥	PART 2 = MAJOR 16	*
	* *	PART 1 :	*
	*	MUX CONTROL & ROM -> OSPE LOGICAL FAULTS - MINORS I THRU 7	*
	*	ROM -> DSPL SHORTS - MINORS 8 THRU 71	*
	*		*
	*****	***************************************	****
00		INITIALIZE	
		DEFINE SELF TEST TAPE	
		ENABLE LUW LEVEL ON GTCCOl*	
01		TEST BREG = ZERO -> DSPL => DSPL = BLANK	
		INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBE7FU7FF STOP TAPE	TREG->ROM, ROM DSPL
02		TEST BREG = FFFFFFFF HEX -> DSPL => DSPL = 377777777777	
		LUAD A REGISTER WITH FEFFFFF	
		INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH DEBEFEOF7F	
		INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBF7F07FF	BREG->ROM, ROM DSPL
		STOP TAPE	
03		TEST CREG = FFFFFFFF HEX -> DSPL => DSPL = 37777777777, NO-GO IND	
		SERIALLY LOAD THE B REGISTER WITH AFFFFFFF COMPARE THE B REGISTER TO 5	
		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
04		TEST AREG = ZERO -> DSPL => DSPL = BLANK	
		LUAD A REGISTER WITH 00000000	
		INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH DEBETFOFFF	ROM->DSPL
		STOP TAPE	• • •
¥ 05		TEST AREG = ZERO -> OSPL, BREG = FFFFFFFF, CREG = ZERO => DSPL = BLANK	
		LOAD A REGISTER WITH FFFFFFF	
		INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OPPEFFOF7F	ROM->RIM
		LOAD A REGISTER WITH 00000000	
		INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBF7F0FFF STOP TAPE	R34->D5PL
+ 06		TEST AREG = ZERO -> DSPL, BREG = ZERO, CREG = FFFFFFFF => DSPL = BLANK	

IESTIDECISION   NO.1_LEVEL1			REMARKS
		COMPARE THE B REGISTER TO 5 LOAD A REGISTER WITH 0000000 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH DEBEFEDERF INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH DEBEFEDEFE STOP TAPE	QDM-SRIM ROM-SDSPL
14 07		AREC = FFFFFFFF -> DSPL, BREG = CREG = ZERO => DSPL = 3777777777 SERIALLY LOAD THE B REGISTER WITH A COMPARE THE B REGISTER TO A LOAD A REGISTER WITH 00000000 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFF0F7F	ROM->RIM
		LOAD A REGISTER WITH FFFFFFF INITIATE SELF TEST MODE 2~LOAD SELF TEST REGISTER WITH OFBF7F0FFF STOP TAPE	ROM->DSPL
-14- st	****	*****	****
**	*****	~~~~ <del>~</del> ~~ <del>~</del> ~~~~~~~~~~~~~~~~~~~~~~~~~~	***************************************
*		TEST FOR SHORT IN ROM -> DSPL, MINORS 8 - 71	*
*		PROCEED PER PARAGRAPH 3-4	*
**	*****	***************************************	* ***********
14 08		DSPL =20000000000 Serially Load the B register with A Compare the B register to 2	
14 09		COMPARE THE 8 REGISTER TO DEFEFFF	
14 10		DSPL = 1000000000 COMPARE THE B REGISTER TO E	
14 11		DSPL =27777777777 COMPARE THE & REGISTER TO IFFFFFF	
14 12		DSPL =400000000 COMPARE THE B REGISTER TO 8	
14 13		DSPL =33777777777 Compare the B register to 7FFFFFF	
14 14		DSPL =2000000000 Compart the 5 register to b	
14 15		USPL =35777777777	

TESTIDECISION   TEST/FAUL		REMARKS
	COMPARE THE 8 REGISTER TO 4FFFFFF	
14 16	DSPL =1000000000 Compare the B register to A8	
14 17	DSPL =36777777777 COMPARE THE B REGISTER TO 57FFFFFF	
14 18	DSPL =400000000 Compare the B pegister to A4	
14 19	DSPL = 37377777777 COMPARE THE E PEGISTER TO 58FFFFFF	
14 20	DSPL =200000000 COMPARE THE B PEGISTER TO A2	
14 21	DSPL =37577777777 Compare the b register to 5DFFFFFF	
14 22	COMPARE THE B REGISTER TO AL	
14 23	DSPL = 3767777777 Compare the B register to seffeffe	
14 24	DSPL =40000000 COMPARE THE B REGISTER TO A08	
14 25	DSPL = 37737777777 COMPARE THE B REGISTER TO 5F7FFFFF	
14 26	DSPL =20000000 Compare the B register to A04	
14 27	DSPL =37757777777 Compare the R register to 5FBFFFFF	
14 28	DSPL = 10000000 COMPARE THE D PEGISTER TO A02	

ITEST DECISION   TEST/FAULT  _NO_1_LEVE!NUMBER	I SELF-TEST PROGRAM	REMARKS
14 29	DSPL ≠3776777777 COMPARE THE B REGISTER TO 5FDFFFFF	
14 30	DSPL =4000000 COMPARE THE B REGISTER TO A01	
14 31	OSPL =37773777777 COMPARE THE B REGISTER TO SEEFEEF	
14 32	ESPL =2000000 COMPARE THE P REGISTER TO A008	
14 33	DSPL =3777577777 COMPARE THE B REGISTER TO 5FF7FFFF	
14 34	DSPL =1000000 Compare the B register to A004	
14 35	OSPL =37776777777 Compare the B register to SFFBFFFF	
14 35	DSPL =400000 Compare the r register to 4002	
14 37	USPL =37777377777 COMPARE THE B REGISTER TO SEEDFEFF	
14 30	OSPL =200000 COMPARE THE B PEGISTER TO AGO)	
14 39	DSPL =37777577777 Compare the 8 register to Sfreefff	
14 40	DSPL =100000 CUMPARE THE B REGISTER ID ACODE	
I÷ ∻1	CSPL =37777677777 COMPARE THE B REGISTER TO SEFFYEE	
) a. 42	DSPL =40000	

TESTIDECISION   TEST/FAULT		REMARKS
	COMPARE THE E PEGISTER TO A0004	
14 43	DSPL =37777737777 Compare the B register to Sefebre:	
14 44	DSPL =20000 Compart the B register to A0002	
14 45	DSPL =37777757777 Compare the B recister to speedfef	
14 46	DSPL =10000 COMPARE THE B REGISTER TO A0001	
14 47	DSPL = 37777767777 COMPARE THE B REGISTER TO SEFFEREF	
14 48	DSPL =4000 Compare the R-Register to A00008	
14 49	DSPL =37777773777 COMPARE THE B RECISTER TO 5FFFF7FF	
14 50	DSPL =2000 COMPARE THE B REGISTER TO A00004	
14 51	DSPL =37777775777 COMPARE THE B REGISTER TO SFFFFBFF	
14 52	DSPL =1000 COMPARE THE B PEGISTER TO A00002	
14 53	DSPL = 37777776777 COMPARE THE B REGISTER TO SEFFEDEE	
14 54	DSPL =400 Compare the r proister to A00001	
14 55	DSPL =37777777377 COMPARE THE B RECISTER TO SEFFEEF	

TESTIDECISION   TEST/F		REMARKS
14 56	CSPL ≈200 Compare the B register to A000008	
4 57	DSPL #37777777777 COMPARE THE B REGISTER TO 5FFFFF7F	
14 58	DSPL #100 Compare the B begister to A000004	
14 59	DSPL #3777777677 COMPARE THE 8 REGISTER TO SEFFFF8F	
14 60	COMPARE THE B REGISTER TO A000002	
14 61	CSPL =37777777737 COMPARE THE 8 REGISTER TO SEFFEFDE	
14 62	DSPL =20 COMPARE THE B REGISTER TO A000001	
14 63	DSPL = 3777777775? Compare the B pegister to 5FFFFFEF	
14 64	DSPL =10 Compare the B register to A0000008	
14 65	DSPL =37777777767 Compare the e register to SFFFFFF7	
14 66	CSPL =4 Compare the B register to A0000004	
14 67	DSPL = 3777777777 COMPARE THE B REGISTER TO SFFFFFB	
14 68	DSPL ≠2 COMPARE THE B REGISTER TO A0000002	
]4 69	DSPL =37777777775	

11957, DEGISION   TEST/FAULT   1021   11961   NUMEER	SELF-TEST P	PROGRAM	REMAR(S	.1
	COMPARE THE B POSISTER TO SEFFERED			
14 /0	CSPL =1 COMPARE THE B RECISTIR TO ADDODD1			
14 71	DSPL =37777777775 COMPARE THE B RECISTLE TO SEFEREE			
14 72	COMPARE THE REPEGISTER TO A FND OF MAJOR TEST			

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	SION   TEST/FAULT VELNUMBER		REMARKS
		************	
	*		*
	*	MANUAL ANALUG TESTS	*
	*	MAJOR 15	*
		*****************	•
5 00		DEFINE SELF TEST TAPE	
		SET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST NCU CLOCK MODE (GTCOC3*)	
		ENABLE LOW LEVEL ON GTCOOI*	
5 61		SERIALLY LOAD THE B REGISTER WITH A408000F	SEY UP 4.7VDC TEST IF NO TRANS A->B
		LOAD ANALOG CUNTROL WORD WITH AOOPO	TEST MONITOR SW & BUFF AMP SAT WITH NO CHANNELS EN
		RESET ANALOG CONTROL WORD	
02		LOAD A REGISTER WITH AFFFFFF	SET UP DATA TO BE CLEARED
		LOAD ANALOG CONTROL WORD WITH A4080	TEST +15VDC
		COMPARE THE & REGISTER TO A4080	TEST FOR AREG CLEARED
		BRANCH TO MAJOR 15 MINOR 37 ON NO-SO	
5 03		RESET ANALOG CONTROL WORD	
		STOP TAPE	TEST CLEAR OF ANALOG CONTRO
5 04		LUAD ANALOG CONTROL WORD WITH A2080	WORD TEST 26VAC
		EGAP ARAEOG CONTROL WORD WITH A2000	1.51 20440
	****	« · · · · · · · · · · · · · · · · · · ·	****
	¥		*
	*	LOW LEVEL CHANNELS TESTS	*
	*	*********************	* *******
5 05		LOAD DISCRETE INPUT WORD (EIP/EDP CODE) WITH A00080 LUAD ANALOG CONTROL WORD WITH A9080	SET 28V ANALOG SW
06		LOAD ANALOG CONTROL WORD WITH A9580	D.A.ERROR L.S.ERROR
07		LOAD ANALOG CONTROL WORD WITH A8880	G.S.ERROR
5 08		LOAD ANALOG CONTROL WORD WITH A8280	DEV
5 09		LOAD ANALOG CONTROL WORD WITH A8180	AZ C. ERRER
	****	*******	
	*		*
	*	DC VOLTAGE CHANNELS TESTS	*
	44		*
	*******	***************************************	*****
5 10		LOAD ANALOG CONTROL WORD WITH A0082	+30VDC, 2UV:30
5 11		LOAD ANALOS CONTROL WORD WITH ACCC2	+30VDC, QUV230
5 12		LOAD ANALOG CONTROL WORD WITH A0042	+12VDC, QUV112
513		ŁOAD ANALOG CONTROL WORD WITH AODEZ	-06VDC+ 20V106
5 14		LOAD ANALOG CONTROL WORD WITH A0092	+1ZVDC, QUV212

TESTIDECT	ISTON   TEST/FAULT EVELNUMBER	I SELF-TEST PROGRAM	REMARKS
5 1 5		LOAD ANALOG CONTROL WORD WITH A0002	-06VDC, QUV206
5 16		LOAD ANALOS CONTROL WORD WITH ACOB2	+05VDC, 00V105
5 17		LOAD ANALOG CONTROL WORD WITH AOOF2	+05VDC, 2UV205
	****	**************	*****
	*		*
	<b>*</b>	SYNCHRO CHANNELS TESTS	*
	* *******	* * * * * * * * * * * * * * * * * * * *	~ *****************
5 18		LUAD ANALOG CONTROL WORD WITH A0088	R \$\$000
5 1 9		LOAD ANALOG CONTROL WORD WITH ACOCS	RSS001
5 20		LOAD ANALOG CONTROL WORD WITH ADDA8	R\$\$002
5 21		LOAD ANALOG CONTROL WORD WITH AODE8	۹\$\$003
5 22		LOAD ANALOG CONTROL WORD WITH A0098	RSS008
5 23		LOAD ANALOG CONTROL WORD WITH ADOD8	R \$\$009
5 24		LOAD ANALOG CONTROL WORD WITH AOOB8	P \$\$010
5 25		LOAD ANALOG CONTROL WORD WITH ADDER	RSSO11
5 26 5 27		LUAD ANALOG CONTROL WORD WITH A0084	R\$\$006
5 28		LOAD ANALOG CONTROL WORD WITH ACCC4	R \$ \$ \$ 007
5 2 9		LOAD ANALOG CONTROL WORD WITH AOOA4 LOAD ANALOG CONTROL WORD WITH AOOE4	RSS012 RSS013
5 30		LOAD ANALOG CONTROL WORD WITH A0094	35013
5 31		LOAD ANALOG CONTROL WORD WITH A0004	RSS005
5 32		LOAD ANALOG CONTROL WORD WITH ADDE4	R\$\$005 R\$\$014
5 33		LOAD ANALOG CONTROL WORD WITH ADDF4	355015
	******	***********************	******
	*		*
	*	TESTS OF INACTIVE CONTROL WORD	*
	*		*
	****	***************************************	*****
5 34		LOAD ANALOG CONTROL WORD WITH A4000	MONITOR SW NOT EN
5 35		LOAD ANALOG CONTROL WORD WITH A8080	ND CHANNELS ENABLED TO PREAMP
536		LOAD ANALOG CONTROL WORD WITH A0880	PREAMP NOT ENABLED TO BUP
5 37		BRANCH TO MAJOR 15 MINOR 38 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A00000	
, ,,		RESET ANALOG CONTROL WORD	
		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON Reset analog control word	
5 20		KESET ANALUG GUNIKUL WUKU	
5 38			
5 38		LCAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A00000 ENABLE VERTICAL PARITY CHECK	

	ION   TEST/FAULT		REMARKS
	****	****************	*****
	* *	MANUAL MULTIPLEXER TESTS- PART 2, PART 1 = MAJOR 14 PROCEED PER PARAGRAPH 3-4	* *
	* *	TEST FOR SHORTS INMX->RIM->BREG	* *
	*******	***************************************	*****
. <del>6</del> 00		INITIALIZE DEFINE SELF TEST TAPE EMABLE LOW LEVEL ON GTC001*	
.6 01		DSPL =2000000000 SERIALLY LOAD THE B REGISTER WITH A COMPARE THE B REGISTER TO 2	
		INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77FOBBF	CREG->ROM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
€ 02		DSPL = 1777777777 COMPARE THE 8 PEGISIER TO FFFFFFF INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F0F8F	CREG->ROM+ ROM->DSPL+ DSPL->INMX, MSHD DSPL -> RIM
.6 03		TSPL =1000000000 LOAD A REGISTEM WITH 3 COMPARE THE B REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F088F	CREG->ROM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
LA 04		DSPL =27777777777 COMPARE THE B PEGISTER TO FEFFFFF INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77FODBF	CREG->RDM, ROM->DSPL, DSPL->INMX, MSHD PSPL -> RIM
16 05		DSPL =400000000 LOAD & REGISTER WITH 9 CUMPARE THE P PEGISTER TO THE A REGISTER INITIATE SELF FLST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F0BBF	CREG->RDM, RDM->DSPL, DSPL->INMX, MSHD DSPL -> RIM

ITESTIDECTSION   TEST/FAULT  _NO_1LEVELNUMPER	SELF-TEST PROGRAM	REMARKS
16 06	DSPL =33777777777 COMPARE THE B REGISTER TO EFFEFFE INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77FORBE	CRES->ROM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
16 07	DSPL =2000000000 LOAD A REGISTER WITH C COMPARE THE P REGISTER TO THE A REGISTER INFITATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77FORBE	CREG->ROM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
16 08	USPL =35777777777 COMPARE THE & REGISTER TO FFFFFFF INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77FORDF	CREG->ROM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
16 09	PSPL =1000000000 LOAD A REGISTER WITH E7 COMPARE THE B PEGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77FOBBF	CRES->ROM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
16 10	FSPL =36777777777 COMPARE THE B PEGISTER TO FEFFFEF INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77FOBBF	CREG->RDM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
16 11	DSPL =400000000 LOAD A REGISTER WITH F3 COMPARE THE D REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F08BF	CREG->RDM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
16 12	DSPL #3737777777 LOAD A REGISTER WITH FFFFFF COMPARE THE E REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F088F	CREG->ROM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM

TESTIDECISION   TEST/FAULT NO.1 LEVEL NUMBER		REMARKS
14 13	DSPL =200000000 LOAD A REGISTER WITH F9 COMPARE THE R REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F088F	CREG~>ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
16 14	DSPL = 37577777777 LOAD A REGISTER WITH FFFFFF COMPARE THE R REGISTER TO THE A REGISTER INITIATE SELF FEST MODE 1-LOAD SELF TEST REGISTER WITH DEB77FOBBF	CREG->RDM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
16 15	DSPL =100000000 LOAD A REGISTER WITH FC COMPARE THE R REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F0B3F	CRES->RDM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
16 16	DSPL #37677777777 LUAD A REGISTER WITH FFFFFFF COMPARE THE B REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1~LOAD SELF TEST REGISTER WITH OFB77F083F	CRES->ROM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
16 17	DSPL =40000000 LOAD & REGISTER WITH FE7 COMPARE THE B REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F0BBF	CRE3->ROM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
16 18	DSPL =37737777777 LOAD A REGISTER WITH FFFFFF COMPARE THE B REGISTER TO THE A REGISTER INITIATE SELF TEST MUDE 1-LOAD SELF TEST REGISTER WITH DFB77FOBBF	CRE3->ROM; ROM->DSPL; DSPL->INMX; MSHD DSPL -> RIM
16 19	DSPL #20000000 LUAD A REGISTER WITH FF3 COMPARE THE B REGISTER TO THE A REGISTER INITIATE SELF 1EST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F08BF	CREGH->RUM; ROM->DSPL; DSPL->INMX; MSHD DSPL +> RIM

TESTIDECISION   TEST/FAULT		₹
16 20	DSPL =37757777777 LOAD A REGISTER WITH FEFEFE COMPARE THE B REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F03RF	SRES->ROM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
16 21	DSPL =10000000 LOAD A REGISTER WITH FF9 COMPARE THE B PEGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F0RBF	CREG->ROM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
16 22	DSPL =37767777777 LOAD A REGISTER WITH FFFFFF COMPARE THE B REGISTER TO THE A REGISTER INITIATE SELL TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F0B3F	CREG->ROM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
16 23	DSPL =4000000 LOAD A REGISTER WITH FFC COMPARE THE P REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F0BBF	CRES->ROM, RGM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
16 24	DSPL ≈37773777777 LOAD & REGISTER WITH FFEFFF COMPARE THE B REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F083F	CRES->ROM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
16 25	PSPL =2000000 LOAD A REGISTER WITH FFE7 COMPART THE B REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F088F	CREG->ROM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
16 26	LSPL =37775777777 LOAD A REGISTED WITH FFFFFF COMPARE THE R REGISTER TO THE A REGISTER INITIATE SELF TOST MODE 1-LOAD SELF TEST REGISTER WITH OF077F086F	CREG->ROM+ ROM->DSPL, DSPL->INMX, MSHD DSPL ->

TESTICECISION   TEST/FAULT _NC.1LEVEL _1NUMBER	I SELF-TEST PROGRAM	PEMARKS
		र्ग्र
6 27	ESPL =1000000 LOAD A REGISTE? WITH FFF3 COMPARE THE B REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F08BF	CREG->RDM, RGM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
6 28	DSPL =37776777777 LOAD A RECITYES WITH FFFFF COMPARE THE B RECISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77FOEBF	CREG->RAM, RAM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
6 29	DSPL =400000 LGAD A REGISTER WITH FFF9 COMPARE THE B REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F08BF	CREG~>RDM+ RDM->DSPL; DSPL->INMX; MSHD DSPL -> RIM
6 30	DSPL =37777377777 LOAD A REGISTER WITH FEFFE COMPARE THE 8 REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1~LOAD SELF TEST REGISTER WITH OF877F088F	CREG->RAM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
5 31	DSPL =200000 LOAD A REGISTER WITH FFFC COMPARE THE & REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F080F	CREG->ROM: ROM->DSPL; DSPL->INMX; MSHD DSPL -> RIM
6 32	DSPL =37777577777 LOAD A REGISTER WITH FFFFF COMPARE THE B PEGISTER TO THE A REGISTER INITIALE SELF TEST MODE I-LOAD SELF TEST REGISTER WITH OFB77FORBF	CREG->ROM+ ROM->DSPL+ DSPL->INNX+ MSHD DSPL -> RIM
6 33	CSPL =100000 LOAD A REGISTER WITH FFFE7 COMPARE THE & REGISTER TO THE A REGISTER	

TESTIDECISION   TESTZFAULT	SELF-TEST PROGRAM	REMARKS
	INTELATE SELF TEST MODE 1-LOAD SELF TEST RESISTER WITH OF577FORBE	CRECHERON, ROMHEROSPL, DSPLHEINMX, MSHD DSPLHE RIM
16 34	DSPL #37777677777 LOAD A REGISTER WITH FEFSE COMPART THE 6 REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH CEB77FOBBE	CREGH>ROM, ROM->DSPL, DSPL->INMX, MSHD PSPL -> RIM
16 35	DSPL =40000 LOAD A REGISTER WITH FEFF3 COMPARE THE B PECISTER TO IME A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F088F	CREG>RUX, ROM->DSPL, DSPL->INMX, MSRD DSPL -> RIM
16 36	USPL =37777737777 LOAD A REGISTER WITH FFFF COMPARE THE & REGISTER TO THE A REGISTER INITEATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OF877FC0BF	CREC->ROM→ ROM->OSPL, OSPL->INMX⊽ MSHO DSPL -> RIY
16 37	PSPL =20000 LOAD A REGISTER WITH FEFF9 COMPARC THE & REGISTER TO THE A RESISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST RESISTER WITH OFB77F038F	CREG->ROM, ROM->DSPL, DSPL->INMX, MSHO DSPL -> RIS
16 38	CSPL =37777757777 LOAD & REGISTER WITH FFFF COMPARF THE B REGISTER TO THE A REGISTER INITIATE SELF TEST MODE I-LOAD SELF TEST REGISTER WITH OFB77F0BBF	CREG->ROM+>DSPL; DSPL=>INMX; MSHD DSPL +> RIM
16 39	ESPL =10000 LOAD A REGISTER WITH FFFFC COMPARE THE B REGISTER TO THE A REGISTER INITIATE SELF TEST MODE I-LOAD SELF TEST REGISTER WITH OFB77F0B3F	CREC->RDN; ROM->DSPL; DSPL->INMX; MSHD DSPL -> RIM
16 40	(SOL = 3777767777	

ITESTIDECISION   TEST/FAULT		I REMARKS
	LOAD A REGISTER WITH FFFF Compare the 8 register to the A register Initiate self test mode 1-load self test register with ofb77fobbf	CREG->RDM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
16 41	DSPL =4000 LOAD A REGISTER WITH FFFFE7 COMPARE THE & REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F0BBF	CREG->RDM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
15 42	CSPL =37777773777 LOAD A REGISTER WITH FFFF COMPARE THE B REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F08BF	CREG->ROM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
.6 43	DSPL =2000 LOAD A REGISTER WITH FFFFF3 COMPARE THE B REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F0BBF	CREG->ROM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
6 44	CSPL =37777775777 LOAD A REGISTER WITH FFF COMPARE THE & REGISTER TO THE A REGISTER INITIATE SELF "EST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F0BBF	CREG>ROM, ROM>DSPL, DSPL->INMX, MSHD DSPL -> RIM
.6 45	DSPL =1000 LOAD A REGISTER WITH FFFFF9 COMPARE THE B REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F0BBF	CREG>RDM, ROM>DSPL, DSPL->INMX, MSHD DSPL -; RIM
16 46	DSPL =3777776777 LOAD A REGISTE® WITH FFF COMPARE THE E REGISTER IO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F088F	CREG~>ROM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM

TESTICECISION   TEST/FAU		REMARKS
16 47	DSPL =400 LOAD A REGISTER WITH FFFFC COMPARE THE B REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1~LOAD SELF TEST REGISTER WITH OFB77F0BBF	CREG->RDM, ROM->DSPL, RSPL->INMX, MSHD DSPL -> RIM
16 48	DSPL =37777777377 LOAD A REGISTER WITH FFF COMPARE THE B REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77FOBBF	CREG->ROM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
16 49	DSPL =200 LOAD A REGISTER WITH FFFFFE7 COMPARE THE B REGISTER TO THE A REGISTER INITIATE SELF JEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F0BBF	CREG->RDM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
16 50	DSPL =3777777777777 LOAD A REGISTER WITH FEF COMPARE THE B REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77FORBF	CREG->ROM; ROM~>DSPL; DSPL->INMX; MSHD DSPL -> RIM
16 51	DSPL =100 LOAD A REGISTER WITH FFFFFF3 COMPARE THE & REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OF677F086F	CREG->RDM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
16 52	DSPL =377777777677 LOAD A REGISTER WITH FF COMPARE THE B REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F088F	CREG->RDM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
16 53	USPL #40 LOAD A REGISTER WITH FFFFFF9 COMPARE THE B REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F0PBF	CREG->RDM, ROM->DSPL, DSPL->INMX, MSHD DSPL ->

TESTIDECISION   TEST/FAULT		I REMARKS
		RIM
6 54	DSPL = 3777777773? LOAD A REGISTER WITH FF COMPARE THE B REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OF077F088F	CREG->ROM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
16 55	DSPL = 20 LOAD A REGISTER WITH FFFFFC COMPARE THE B PEGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH DF877F088F	CREG->RDM, ROM->DSPL, DSPL->INMX, MSHD PSPL -> RIM
16 56	DSPL =377777777757 LOAD & REGISTER WITH FF COMPARE THE B REGISTER TO THE A REGISTER INITIATE SELF PEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F0BBF	CREG-DROM, ROM-DDSPL, DSPL-DINMX, MSHD FSPL -D RIM
16 57	DSPL =10 LOAD A REGISTER WITH FFFFFFE7 COMPARE THE B REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F088F	CREG~>ROM, ROM~>DSPL, DSPL->INMX, MSHD DSPL ->
16 58	DSPL #3777777767 LOAD A REGISTER WITH FF COMPARE THE B REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F08BF	RIM CRES->ROM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
16 29	DSPL =4 LOAD A REGISTER WITH FFFFFF3 COMPARE THE B REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 4-LOAD SELF TEST REGISTER WITH OFB77F083F	CREG->ROM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
26 60	DSPL =37777777773 LOAD A REGISTER WITH F COMPARE THE 5 REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OF877F088F	CRES->ROM, ROM->DSPL, DSPL->INMX, MSHD DSPL ->

ITESTIDECISION   TEST/FAULT  _NO_ILEVELINUMBER	SELF-TEST PROGRAM	REMARKS
		RIM
16 61	DSPL =2 LOAD A REGISTER WITH FFFFFF9 COMPARE THE B PEGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER STATE OFB77F088F	CRES->ROM, ROM->DSPL, DSPL->[NMX, MSHJ DSPL -> RIM
16 62	DSPL =37777777775 LOAD A REGISTER WITH F COMPARE THE B PEGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F0BBF	CRES->ROM, ROM->DSPL, DSPL->[NMX, MSHD DSPL -> RIM
16 63	DSPL =1 LOAD & REGISTED WITH FFFFFFC COMPARE THE B REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77FOBBF	CRES->ROM, ROM->DSPL, DSPL->INMX, MSHD DSPL -> RIM
16 64	CSPL =37777777776 LOAD A REGISTER WITH F COMPARE THE B REGISTER TO THE A REGISTER INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F0P8F	CREG->ROM, ROM->DSPL, DSPL->INMX, MSHJ DSPL -> RIM
16 65	END OF MAJOR TEST	

	IN   TEST/FAULT NUMBER		I REMARKS
	****	*******************	*****
	*		*
	*	CIU POSFIX PULSE TESTS, GTCOC1* -> QUUOO1* => POSFIX PULSE	*
	*		*
	*	MAJOR 17	*
	*		*
	*	1. CLK (CUN TAPE STOP TESTS	*
	*	2. POSFIX ERROR STOP TESTS	*
	*	3. POSFIX PULSE WIDTH TESTS	*
	*	4. CONDITIONAL CLK RUN TESTS	*
	*	THIS MAJOR NUBBER ALSO USED FOR TEST/FAULT LOC AFTER MAJOR 99	*
	*		*
	***	****	*****
7 00		DEFINE SELF TEST TAPE	
		SET INHIBIT INCREMENT OP FLAG & ENABLE SELF TEST NOU CLOCK MODE	
		(GTC003*)	
		ENABLE LOW LEVEL ON GTCOOL*	
	*****	<b>谢操女学者学者学校学校学校教育教育学校学校学校学校学校教育学校教育学校教育学校教育学校教育学校</b>	·************************************
	*		*
	*	CLK RUN TAPE STOP TESTS	*
	*		*
	******	***************************************	********
7 01		INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFEOFFF	CLK RUN TAPE STOP
		ENABLE CONTROLLED TIMING PULSE INTERVAL 10 ON GTC001*	
		BRANCH TO MAJOP 17 MINOR 3	
		} ,	
7 02 2	F30.1	AUTO SECTION FAUL' LOC - FAULT IN 3SB OF MABC	
		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		I INCIGATORS I DISPLAY I REPLACE ASSEMBLIES	
		IND_GOIBLANKIIAIAIA(21,22)	1
7 03		INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFEOFFF	CLK RUN TAPE STOP
		ENABLE CONTROLLED TIMING PULSE INTERVAL 10 CONDITIONALLY ON GTC001*	

	I TEST/FAULT		I REMARKS
	**************	***********	******
-	*	POSFIX ERROR STOP TESTS	*
	<b>*</b>		*
	******	***************************************	******
7 04		INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFEOF7F	CLK RUN TAPE STOP, POSFIX PULSE CHECK
		ENABLE CONTROLLED TIMING PULSE INTERVAL 2 CONDITIONALLY ON GTCODI*	
7 05		INITIATE SELF TEST MUDE 2-LOAD SELF TEST REGISTER WITH OFBFFEOF7F	CLK RUN TAPE STOP, POSFIX
		ENABLE CONTROLLED FIMING PULSE INTERVAL 999 CONDITIONALLY ON GTCOOL*	PULSE CHECK
7 06		INITIATE SELF LEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFEOF7F	CLK RUN TAPE STOP, POSEIX PULSE CHECK
		ENABLE CONTROLLED TIMING PULSE INTERVAL 10 ON STCOOI*	PULSE WIDTH ALMOST SHORT ENDUGH
		***************************************	
	<b>∻</b>	POSFIX PULSE WIDTH TESTS	* *
:	*	COSTIN FOLST MIDIN (LSIS	*
,	******	***************************************	*****
7 07		INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFEOF7F	CLK RUN TAPE STOP, POSETX PULSE CHECK
		ENABLE CONTROLLED TIMING PULSE INTERVAL 3 CONDITIONALLY ON GTCOOL*	PULSE WIOTH ALMOST LONG ENOUSH
7 08		INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFE0F7F	CLK RUN TAPE STOP, POSFIX PULSE CHECK

 17 09
 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFE0F7F
 CLK RUN TAPE STDP, POSFIX PULSE CHECK

 ENABLE CONTROLLED TIMING PULSE INTERVAL 9 ON GTC001\*
 PULSE WIDTH ALMOST TOO LONT

TESTICECISION 1		SELF-TEST PROGRAM	REMARS
***	******	******	
*		CONDITIONAL CLK RUN TESTS	*
***	*********	****************	*********
17 10		SERIALLY LOAD THE B REGISTER WITH A03 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH 4FBFFE077F	RDH->CH#DR, CLK RUN TAPE Stop, breg->rom,posfix pls
		ENABLE CONTROLLED TIMING PULSE INTERVAL 16 CONDITIONALLY ON GTCOO1*	Сн
17 11		SERIALLY LOAD THE B REGISTER WITH A03 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH 4FBFFE077F	ROM->CM#DR, Clk RUN TAPE Stop, Breg->Rom,Posfix pls CH
		ENABLE CONTROLLED TIMING PULSE INTERVAL 12 CONDITIONALLY ON GTCOOL*	
17 12 17 13		ENABLE VERTICAL PARITY CHECK END OF MAJOR TEST	

ITESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
I NOAT I EVEL I NUMBER		1
<u>، « في معاط يا بالا الحيد في من التا ما مع في الا الم</u>		

	***********************	******
	* EIP/EOP MANUAL TESTS (FAULT ISOLATION) * Major 18	* * *
	* 1. (EOP) PJB>B, STOP, CISPLAY B - NO GO * 2. (EOP) PJB>B, DISPLAY B - STOP * 3. (EOP) PJB>B, STOP, ENABLE ANALOG CONTROL WORD, 4.7VDC * 4. (EOP) BLANK ANALOG CONTROL WORD *	* * * * *
18 00	DEFINE SELF TEST TAPE Set invibit increment CP flag & enable self test nou clock mode (btc003*) Enable low level on gtc001*	
18 01	SERIALLY LOAD THE & REGISTER WITH A029CBB8 Initiate self test mode 2-load self test register with &fbfffofff Load discrete input word (Eip/Edp Code) with A3B200 Load discrete input word (Eip/Edp Code) with A3B00	RDM->W1 DR EA =354 Octal EOP PJB->B, Stop, DSPL B, ND-GO
18 02	SERIALLY LOAC THE B REGISTER WITH A7D63447 Initiate SELF Test Mode 2-Load SELF Test register with 8FBFFF0FFF Load discrete input Word (EIP/EQP Code) with A38600 Load discrete input Word (EIP/EQP Code) with A38400	ROM->W1 DR EA ≈355 GCTAL EOP PJB->8, STOP, DSPL P
18 03		
	LDAD DISCRETE INPUT WORD (EIP/EDP CODE) WITH A00200 Serially load the B register with A3e8	I/O REQ INACTIVE Set up ea=372 Octal to be Loaded breg->Dihr on Losi
	INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH BFBFFF07FF Laad discrete input word (EIP/EDP Code) with ABF7FFFF	RDM->WD1 DR, BRE3->RDM EOP PJB->B, STOP, EN ANALDS CONTROL WD- DATA TRANS= AREG->RDM->WD1* DR->PJP REC->BREG->ANALJG CONTROL WORD =4080 = 15VD' TEST
18 04	LDAD DISCRETE INPUT WORD (EIP/EDP CODE) WITH A3EE00 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3EC00 STOP TAPE	EA=373 OCTAL EGP BLANK ANALOG CONTROL WORD

ITESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	REMARKS
I_NOAL_LEVEL_L_NUMBERL		
10.05		

18 05	ENABLE VERTICAL PARITY CHECK
18 06	END OF MAJOR TEST

TESTIDECISION	I TEST/FAULT	SELF-TEST PROGRAM	REMARKS
1	* <b>********</b> *****	***************************************	***************************************
1	* •	ISULATE FAULT IN TST2	*
3		MINORS 3 - 37 TESTS (00)T3.6.NN MINORS 50 - 73 EXTENSION OF INITIAL CONFIDENCE TESTS	*
•	, , ,	MINURS 30 - 15 EXTENSION OF INITIAL CONFIDENCE TESTS	*
	•••••		
9002	F30.2 F72.1	FAULT IN 3SB OF MABC, OR BBC536* INPUT TO MBC061 S@1	
		I INDICATORS I DISPLAY ISEPLACE_ASSEMBLIES IIESI_SEI_EAULI_12100000000011A1A1A121.221	1 1
		PUNCH TAPE LEACER 12 INCHES LONG	
		INITIALIZE - DEFINE SELF TEST TAPE ENABLE LOW LEVFL ON GTCOOI* BRANCH TO MAJOR 19 MINOR 50	
9 01 9 02		STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT DN Stop Tape, Display C register, ND-go light on	
9034	(00)T3.6.N	TEST FOR RESET OF TST2(SIM ND-GO) ON CMA121 OR KTL501 WITH NO EN OF CMA121 OR KTL501	
9 04		SERIALLY LOAD THE B REGISTER WITH AAAAAAAAA INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBF014FFF	RESET SIM NO-GC DN CMA121 7 . KTL501
		BRANCH TO MAJOR 19 MINOR 22 ON NO-GO	NO-30 = PASS
9055	T3.6.NNG	TEST RESET OF TST2(SIM NO-GD) WITH NO MEM LD BREG CONTROL EN Set the I/O complete flag (Gtcolo*) Reset the I/U complete flag (Gtcolo*)	RESET TST2
		INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF3F014FFF Branch to Majof 19 Minor 6 ON NO-GO. Branch to Major 19 Minor 7	SIM ND-GD, INH ALL MEH EN ND-GO = PASS
9 06 6	T3.6.NNGN	FAULT IN CMA121 OR KTL501, ACTIVE => RESET TST2 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON-	

TESTIDECISION	TEST/FAULT 1NUMBEB	I         SELF-TEST         PROGRAM	REMARKS
		IINDICATORS I DISPLAYIBEPLACE_ASSEMBLIESI IND_GOIBLANKIPROCEED_PER_PARAGRAPH_3-12DI	I
9076 908	T3.6.N∜GG	TEST FOR LOAD OF BREG WITH NO MEM LO BREG EN SERIALLY LOAD THE B REGISTER WITH AAAAAAAA INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF3F014FFF COMPARE THE E REGISTER TO THE A REGISTER BRANCH TO MAJOR 19 MINOR 9 ON NO-GO BRANCH TO MAJOP 19 MINOR 13	SIM NO-GO, INH ALL MEM EN
9 09 7	F3.6.NNGGN	FAULT IN RESET OF TST2 & SELF TEST LOAD OF BREG ACTIVE Set inhibit increment CP flag & enable self test nou clock mode	
		(GTC003*) Enable vertical parity check Enable the A register to the QJD lines	WILL CAUSE TEST SET FAULT UNLESS ARQ052* IS ACTIVE
		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON         Implicators         Implicators         Itest set fault           Implicators         Implicators         Implicators         Itest set fault           Implicators         Implicators	AYR732* ACTIVE
		IND_GDI2525252525212ALA2AL3	ARQO52* ACTIVE
9 10 9 11 9 12		SP ARE SP ARE SP ARE	
19 13 7	F3.6.NNGGG	NOT A NORMAL FAULT LOC - WITH INH ALL MEM EN, RESET TST2 BUT NO LD BREG WITH ALL MEM EN, LD BREG ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	-
		I INDICATORS I DISPLAY I REPLACE ASSEMBLIES INO GO   BLANK IIAIAZA(11,19,21) 	1

19 14	SPARE
19 15	SPARE
19 16	SPARE
19 17	SP AR E
19 18	SPARE
19 19	SPARE
19 20	SPARE

		I TEST/FAULT	SELF-TEST PROGRAM	REMARKS I
19 21 19 22 19 23	5	T3.6.NNN	TEST FOR RESET OF TST2(SIM NO-GO) ON KMA121 OR ATL421* ACTIVE SET THE I/O COMPLETE FLAG (GTCO10*) RESET THE I/O COMPLETE FLAG (GTCO10*) INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF3F8F4FFF BRANCH TO MAJOR 19 MINOR 28 ON NO-GO	RESET TST2 Reset TST2 on Kma121
19 24	6	F3.6.NNNG	ATL421* OR KMA121 ACTIVE ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I INDICATORS I DISPLAY I	
19 25 19 26 19 27			SP AR E SP AR E SP AR E	
19 28 19 29	6	T3.6.NNNN	TEST FOR RESET OF TST2(SIM NO-GO) ON KMA051 SET THE I/O COMPLETE FLAG (GTCO10*) RESET THE 1/O COMPLETE FLAG (GTCO10*) INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF3F4F4FFF BRANCH TO MAJOR 19 MINOR 34 ON NO-GO	RESET TST2 RESET TST2 ON KMA051 ND-GO = PASS
19 30	7	F3.6.NNNNG	KMAO51 ACTIVE ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDIC&TORSI_DISPLAYI	
19 31 19 32 19 33			SPARE SPARE SPARE	
19 34 19 35	7	T3.6.NNNNN	TEST FOR RESET OF TST2(SIM NO-GO) ON KMAO61 SET THE I/O COMPLETE FLAG (GTCO10*) RESET THE I/O COMPLETE FLAG (GTCO10*) INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF3F2F4FFF BRANCH TO MAJOP 19 MINOR 37 ON NO-GO	RESET TST2 RESET TST2 ON KMAO61 NO-GO = PASS
19 36	8	F3.6.NNNNN >G	KMAO61 ACTIVE EVABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GD LIGHT ON	

TESTIDECISION	I TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
		· · · · · · · · · · · · · · · · · · ·	
		INDICATORS LOISPLAY I REPLACE ASSEMBLIES	
		NO_GOIBLANKIAIA3A(1.201	
19-37 8	F3.6.NNNNN >N		
	>N	NOT A NURMAL FAULT LOC - SIM NO-GO RESET AT MAJ O MIN 1, BUT NOT IN MAJ 19ENABLE VERTICAL PARITY CHECK	
		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		I INDICATORS I DISPLAY I BEPLACE ASSEMBLIES	
		IND GD   BLANK (1A1A2A(14,15,16)	
		1II2A1A2A(1.2.13)	
19 38		SPARE	
19 39		SPARE	
19 40 19 41		SPARE SPARE	
19 42		SP 4R E	
19 43		SPARE	
19 44 19 45		SPARE SPARE	
19 46		SP AR E	
L9 47 19 48		SPARE SPARE	
19 49		SPARE	
19 50 19 51		TEST FOR PREMATURE RESET OF TST1 Serially load the B register with a	
		LOAD A REGISTER WITH AFFFFFF	
		INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFF0F7F Compare the B pegister to the A register	ROM -> RIM
		BRANCH TO MAJOR 19 MINOR 52 ON NO-GO	
		BRANCH TO MAJOR 19 MINOR 58	
19 52		TEST 1/0 CMPLT -> MTW1, GTC010* -> QUT009	
19 53		READ & COMPARE MISCELLANEOUS WORD 1 WITH A008	
		LOGICALLY 'AND' C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS	
		BRANCH TO MAJOR 19 MINOR 54 ON NO-GO	
		FAULT IN AYR714* OR AYCOO3*	
		ENABLE VERTICAL PARITY CHECK Set inhibit increment CP flag & Enable self test NCU clock mode	
		(GTC003*)	
		PUNCH TAPE CODES - /B /4 #F #F #F &C	RCNU FFF
		RESET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST CIU CLOCK MODE (GTCOD3*)	
		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	

TESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	R EMARKS
	INCICATORS       01SPLAY       BEPLACE_ASSEMBLIES         ITEST SET FAULT         2000000   2 A1 A2 A20         I       12A1A3A(12+15+16)         NO GO                 BLANK        1A1A1A04         I       11A1A3A09	GYR707 SƏ1 GPE123* SƏ0
19 54	FAULT = I/O CMPLT ACTIVE ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
	I	CEC499* \$20
19 55 19 56 19 57	SP ARE SP ARE SP ARE	
19 58 19 59	TEST FOR NO MMODE 2 CLK ENM LOAD A REGISTER WITH 060 INITIATE SELF TEST MODE 2-RETAIN PREVIOUS BIT PATTERN IN SELF TEST REG BRANCH TO MAJOR 19 MINOR 65	
19 60	AYR712 SƏ1 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I <u>INDICATORS I DISPLAY I BEPLACE ASSEMBLIES</u> NO GO	I
19 61 19 62 19 63 19 64	SPARE SPARE SPARE SPARE	
19 65 19 66	TEST FOR NO TST2 SET THE I/O COMPLETE FLAG (GTCD10*) RESET THE I/O COMPLETE FLAG (GTCD10*) LOAD A REGISTER WITH 073 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH 069FFF0FFF	RESET TST2 SET UP ADDR = 73 TO BRANG TO IF TST2 LOADS STREG THREE MSHD = BRANCH ADDR
	BRANCH TO ADDRESS LOCATION IN A REGISTER	69 WILL BR TO 73 IF STREG LI 69 IF NO TST2

SPARE

TESTIDECISION   TEST/FAULT _NO_1LEVELLNUBBEB	I SELF-TEST PROGRAM	I REMARKS
9 68	SPARE	
9 69	FAULT IN TST2 IBT'OR FF ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT DN	
	INDICATORS I DISPLAY I BEPLACE ASSEMBLIES INO GO I BLANK IZA1AZAOZ	KYR702* S@1
970 971	SP ARE SP AR E	
9 72	SPARE	
973	FAULT IN AYR752 Enable vertical parity check Stop tape, display c register, no-go light on	
	IINDICAIDRSI_DISPLAYIBEPLACE_ASSEMBLIES IND_GOIBLANKIZA1A3A(15.16)	1
9 74	SPARE	
9 <b>75</b> 9 76	SP ARE SP AR E	
9 77	SPARE	
9 78	SPARE	
979	SPARE	
9 80	SPARE	
9 81	SP ARE	
9 82	SPARE SPARE	
983 984	SPARE	
9 85	SPARE	
9 86	SPARE	
9 87	SPARE	
9 88	SP AR E	
9 89	SPARE	
9 90	SPARE	
9 91	SPARE	
9 92	SP AR E	
9 93	SP ARE	
9 94 9 95	SPARE SPARE	
9 95 9 96	SP ARE	
	SPARE	
9 97		

TESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	REMARKS
I NO.I LEVEL I NUMBER I		

	ENABLE VERTICAL PARITY CHECK
19 99	END OF MAJOR TEST

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ITESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS I
I NO. I LEVEL I NUMBER I		1
· · · · · · · · · · · · · · · · · · ·	· · · · · · · · · · · · · · · · · · ·	*

20 00	BRANCH TO MAJOR 20 MINOR 3
20 01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
20 02	STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT DN
20 03	END OF MAJOR TEST

TESTIDECI	SION   TEST/FAULT VEL1NUMBER	SELF-TEST PROGRAM	I REMARKS
	****************	***************************************	************
	*	INTERNAL MULTIPLEXER TESTS- MAJORS 21 AND 22	*
	*	TEST OF CMAB, AANC, LOAB FUNCTIONS- MINORS 3 THRU 44 OF MAJ 21	*
	*		*
	**********	***************************************	*********
21 00		INITIALIZE	
		DEFINE SELF TEST TAPE Enable low level on gTC001*	
		BRANCH TO MAJOR 21 MINOR 2	
21 01		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
	**************************************	***************************************	***************************************
	*	TEST OF CMAB, LDAB, AANC	*
	*	*******	*
21 02 1	T35	TEST CMAB WITH AREG NOT* BREG *> ND-GO	
21 03		PREVIOUS TEST = (37)T31 Initiate self test mode 1-load self test register with ofbfffoff7	PJB -> RIM, => B REG =
21 03		INITIALE SELF TEST MODE I-LOAD SELF TEST REDISTER WITH OF DIFFORT	AFFFFFF
		COMPARE THE B REGISTER TO ADF00001	CREG = 020FFFFE IF NO FAULT
2	F35.1	FAULT LOC WITHIN TEST T35 - FAULT IN CMAB LOGIC	
		INDICATORS I DISPLAY I REPLACE ASSEMPLIES	4
		ITEST_SET_EAULT_16000012A1A1A(13.14)	1
		ITEST_SET_EAULT_1600012A1A1A12+5+6+10+14+151 ITEST_SET_EAULT_1400012A1A1A(4+10+11+12+14+15	1
		TEST SET FAULT 2000/PROCEED PER PARAGRAPH 3-120	i
1	T35(CONT)	BRANCH TO MAJOR 21 MENOR & ON NO-GO	
2	T35+2	TEST RCPJ, AREG NOT= PREG => ND-GD	
2		READ & COMPARE PJB LINES WITH ADDODODO	CREG = OFFFFFFF IF NO FALL
3	F35.2.1	FAULT LOC WITHIN TEST T35.2 - FAULT IN CLK TO AREG & BREG DURING COMPARE	
-			

IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIES ITESI_SEI_EAULI_I600012A1A1A04 BRANCH TO MAJOR 21 MINOR 5 ON NO-GO FAULT IN CMAB => NO GO COMPARE THE B REGISTER TO 00000000 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I	AREG SAT IF AAR045* NOT SQ
FAULT IN CMAB => NO GO COMPARE THE B REGISTER TO 00000000 STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON I_INDICATORSI DISPLAYIBEPLACE_ASSEMBLIES	AREG SAT IF AAR045* NOT SQ
COMPARE THE E REGISTER TO 0000000 STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON IINDICATORSI_DISPLAYI	AREG SAT IF AAR045* NOT SD
IZAIAZA06 INO_GOIBLANKIZAIAIA01	   ND BRANCH ON NO-GO FLAG,   KATO41* SƏ1   CARO35 SƏO
FAULT AT CMAB 18T, LATCH, OR INPUT TO IARO26* STOP TAPE, DISPLAY C REGISTER, NO-GD LIGHT ON IINDICAIDRSI_DISPLAYI	- - - - - -
SP AR E SP AR E	
TEST LDAB Serially LDAD THE B REGISTER WITH OAAAAAAA	
FAULT LOC WITHIN TEST T36 - FAULT IN RESET OF NO-GO FLAG	_
1 <u>TEST_SET_FAULT_16000012A1A1A113.141</u>	_  [AT144* OR [AT044* SƏ1
• • •	STOP TAPE, DISPLAY C REGISTER, NO-GD LIGHT ON  IINDICATORSI_DISPLAYI

		N   TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
21 11 21 12	2	T36.N	CHECK FOR NO #A->B SHIFT CONTROL" Serially Load the B register with AAAAAAAA Compare the B register to Affffff Branch to Majop 21 Minor 14 on NO-Go	
	3	T36.NG	ISOLATE BETWEEN "A->B SHIFT CONTROL" & "TRANS A->P *" LOAD A REGISTER WITH O INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFFOF7F SERIALLY LOAD THE B REGISTER FROM THE A REGISTER COMPARE THE E REGISTER TO AAFFFFFF BRANCH TO MAJOP 21 MINOR 16 ON NO-GO	ROM -> RIM
	4	F36.NGG	FAULT IN "TRANS A->B" STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
	-		I <u>INDICATORS</u> I <u>DISPLAY</u> I <u>REPLACE_ASSEMBLIES</u> NO GOI BLANK IZAIAIA(3,4) I	ARKO21* SƏ1 OR INPUT TO CRK035 SƏ1
21 13			SPARE	
21 13 21 14	3	F36.NN	FAULT IN "A->E CMPLT", INPUT TO CRK034, SERIAL INPUT TO BREG, OR MSHD OR RIM STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
	3	F36.NN	FAULT IN "A->E CMPLT", INPUT TO CRK034, SERIAL INPUT TO BREG, OR MSHD OR Rim	I   ARK121* OR 4AB313* INACTIVF
	3	F36.NN	FAULT IN "A->E CMPLT", INPUT TO CRK034, SERIAL INPUT TO BREG, OR MSHD OR RIM STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATOBSI_DISPLAYIREPLACE_ASSEMBLIES INO GO I24525252512A1A13,4) II2A1A2A120,261 INO GOI20525252512A1A2A01	   ARK121* OR 4AB313* INACTIVF     CAB013
	3	F36.NN	FAULT IN "A->E CMPLT", INPUT TO CRK034, SERIAL INPUT TO BREG, OR MSHD OR         RIM         STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON         Imdicators	   ARK121* OR 4AB313* INACTIVF     CAB013   AAB014
	3	F36.NN	FAULT IN "A->E CMPLT", INPUT TO CRK034, SERIAL INPUT TO BREG, OR MSHD OR         RIM         STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON         Imidicators	   ARK121* OR 4AB313* INACTIVF     CA5013   AAB014   IAB015
	3	F36.NN	FAULT IN "A->E CMPLT", INPUT TO CRK034, SERIAL INPUT TO BREG, OR MSHD OR         RIM         STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON         Imdicators	   ARK121* OR AAB313* INACTIVF     CAB013   AAB014   IAB015   IAB016   CRK034 INACTIVE OR IRB131
	3	F36.NN	FAULT IN "A->E CMPLT", INPUT TO CRK034, SERIAL INPUT TO BREG, OR MSHD OR         RIM         STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON         IIDICATOBSIDISPLAYREPLACE_ASSEMBLIES         INO GO       1245252525251241414(3,4)         II       1241424(20,261         INO GO       120525252525124142401         INO GO       10525252525124142401         INO GO       1265252525124142401         INO GO       14525252525124142402         INO GO       14525252525124142420         INO GO       14525252525124142420	   ARK121* OR 4AB313* INACTIVF     CA5013   AAB014   IAB015   IAB016

21 15 SPARE

21 16 4 F36.NGN FAULT IN A->B SHIFT CONTROL STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON

	LEVEL	I TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
			I INDICATORSI DI SPLAYI	   Baro32 Inactive
1 17 1 18	1	T3 7	TEST FOR NO INH OF B REG END AROUND Serially load the B register with A5555555 Compare the P register to A5555555 Branch to major 21 minor 19 on ND-GO Branch to major 21 minor 20	
1 19	2	F37.N	NG INH GF & REC END AROUND SHIFT STOP TAPF, DISPLAY C REGISTER, NO-GO LIGHT ON I	   IRB133* Sə1
1 20 1 21	1	38	TEST AANC RESET OF TST2 (SIM NO-GO) Initiate self test mode 2-load self test register with ofbfff4fff Logically 'AND' C register and 00000000 - Result in B & C register	SIM ND-GD
	2	F38.1	FAULT LOG WITHIN TEST T38 (NOT A PROGRAMMED STOP)- ERROR IN AANC FUNC I INDICATORS I DISPLAY I REPLACE ASSEMBLIES ITEST SET FAULT 6000012A1A1A14	1
	1	T38(CONT)	BRANCH TO MAJOR 21 MINOR 23 ON NO-30	
	2	F38.2	FAULT LOC WITHIN TEST T38 (NOT A PROGRAMMED STOP)- AANC NOT RESET	I I INPUT TO AARO23* OPEN
	1	T38(CONT)	BRANCH TO MAJOR 21 MINOR 26	
21 22			SPARE	
21 23	2	F38.3	FAULT IN AANC IBT, LATCH, OR INPUT TO AARO16 Initiate self test mode 1-load self test register with ofbfffof7f Compare the D register to the A register Initiate self test mode 2-load self test register with ofbfffo7ff Stop Tape, display C register, NO-go light on	ROM -> RIM 8 Reg -> Rom

ITESTIDECISION I TEST/FAULT I SELF-TEST PROGRAM I REMARK	5 I				
	· ·				
	1				

I_INDICATORS	I DISPLAY I REPLACE A	SSEYBLIESI
INO GO	BLANK ZALALAO2	AANC IBT PR LATCH
I	I2A1A2A02	
IND_GO	2400000012A1A1A02	I INPUT TO AARO16 Sal

21 25 21 26	1	T39	TEST AANC DATA RESULT (A REG).(C REG)->C REG ALSD ->B REG + A0000000	
21 27			SERIALLY LOAD THE B REGISTER WITH A5555555 Initiate self test mode 2-load self test register with ofbfffof7f	ROM -> RIM, WILL CHANGE HEY
			INITIALE SELF (23) MUDE 2-COAD SELF (23) REDISTER WITH OPDFFFORT	A IN MSD IF CCBT LOADS MSD
			COMPARE THE B REGISTER TO FOOOOFFF	RESULT IN C REG = 5555AAAA
			INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF0F7F	ROM -> RIM, WILL CHANGE HEY A IN MSD IF CCBT LOADS MSD
			COMPARE THE B REGISTER TO THE A REGISTER	RESULT IN C REG = 5555AAAA
	2	T39.1	FAULT LOCATION WITHIN TEST T39 (NOT A PROGRAMMED STOP)- CAN NOT SHIFT END Around	
			INDICATORS I DISPLAY I BEPLACE ASSEMBLIES	
			11EST SET FAULT 140001241414121	
			ITEST SET FAULT   2000 PROCEED PER PARAGRAPH 3-12D	FAULT IN B REG END AROUND CR
			TEST_SET_FAULT_16000012A141414	INH ACTIVE
	1	T39(CONT)	LOGICALLY 'AND' C REGISTER AND 5AAA555D - RESULT IN B & C REGISTER	RESULT IN C REG = 50000008 IF ND FAULT
			BRANCH TO MAJOR 21 MINOR 29 ON NO-GO	
	2	F39.G	FAULT IN C REG,OR AANC SHIFT CONTROL,OR OPEN INPUT TO AARO33* OR BARO42* Stop tape, display c register, nd-go light on	
			INDICATORS I DISPLAY I REPLACE ASSEMBLIES	
			NO GO BLANK2A1A1A(2,3,8,9)	C REG DR C REG CLK
			IND_GDI1252532525212A1A1A04I	ARK112* SƏ1

21 28 2 F35.3 FAULT IN PARTIAL CREG->ROM ENABLE ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON

		I TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS I
			INDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GDI20377777612A1A1A19I	
21 29 21 30	2	T40	TEST FOR OPEN INPUT TO AARO33* OR BARO42* Logically "Ano" c register and 10000000 - result in B & C register Branch to major 21 minor 32 on ND-go	
	2	F40.G	FAULT AT GATE AAR033* OR BAR042* Stop Tape, Dis©Lay C register, ND-go Light On	
			IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIESI IND_GOIBLANKI2A1A1A(2+3)	
21 31			SPARE	
21 32 21 33	1	<b>T</b> 41	TEST AANC CMPLT => LOAD HEX A INTO MSD OF B REG SERIALLY LOAD THE B REGISTER WITH A5555555 Compare the B register to 55A5A5A5 Logically "And" C register and 5FAF5FAF - Result in B & C register Compare the B register to A0A050A0 Branch to Majop 21 Minor 35 on ND-GO Branch to Major 21 Minor 37	RESULT IN C REG = FOFOFOFO
21 34			SPARE	
21 35	2	F41.N	FAULT IN AANC CMPLT OR C REG OR B REG CLK         STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON         I       INCIGATORS I DISPLAY         I       ISTSIDATION         IND GO       I 575102765124141403         INO GO       I XXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXXX	AARO33* SƏ1 Input to crko15 sə1 Crég dr Clk
21 36			SP AR E	
21 37 21 38	1	T42	TEST "CLEAR A REG #1" Serially load the B register with A0000000 Load A register with A5555555 Compare The B register to A Branch to Major 21 Minor 40 on No-go Branch to Major 21 Minor 45	

TESTIDECISION	I TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
39		SPARE	
1 40 2 1 41	T42.N	CHECK "CLEAR A REG #3"WITH EIP A->EB, TAPE INITIATE SELF TEST MODE 2-RETAIN PREVIOUS BIT PATTERN IN SELF TEST REG. LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH AB8600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH AB8600 LOAD A REGISTE® WITH 0555555 LOAD A REGISTE® WITH 0555555 LOAD A REGISTE® WITH 0555555 LOAD A REGISTER TO OFFFFFF BRANCH TO MAJOR 21 MINOR 43 ON ND-GO	NO ACTIVE BITS SET UP EA = 1341 ENABLE I/O CMPLT
3	F42.NG	FAULT IN CLEAR A REG #1 OR CLEAR OF MSHD         STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON         INDICATORS       L DISPLAY         IND GO       I 122525252512A1A1A02         INO GO       I 122525252512A1A1A02         INO.GO       I 122000000012A1A1A17	IAR046* SƏ1 INPUT TO ARA074 SƏ1
. 42		S <sup>D</sup> ARE .	
43 3 .** * *	F42.NN	FAULT IN CLEAR A REG         STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON         I	IAR067* SƏ1 A REG A REG A REG A REG A REG A REG A REG ***************
. 44		SP AR E	



TEST NO.		/FAULT SELF-TEST PROGRAM /IBER	REMARKS
21 45 21 46	1 T43	TEST FOR ACTIVE B REG PE DURING TST2(INACTIVEI SERIALLY LOAD THE B REGISTER WITH AAAAAAAA INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFLOFFF COMPARE THE B REGISTER TO THE A REGISTER BRANCH TO MAJOR 21 MINOR 48 ON NO-GO BRANCH TO MAJOR 21 MINOR 63	ALL MEMORY EN ACTIVE
21 47		SPARE	
21 48 21 49	2 T43.N	CHECK MEMORY EN #5 SERIALLY LOAD THE B REGISTER WITH AAAAAAAA INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF3FIFOFFF COMPARE THE P QEGISTER TO THE A RFGISTER BRANCH TO MAJOR 21 MINOR 51 ON NO-GO	MEM EN U5
	3 T43.NG	CHECK MEMORY EN 96 SERIALLY LOAD THE B REGISTER WITH AAAAAAAA INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF3FD70FFF COMPARE THE B PEGISTER TO THE A REGISTER BRANCH TO MAJOR 21 MINOR 52 ON NO-GO	MEM EN #5
	4 T43.NGG	CHECK MEMORY EN 47 SERIALLY LOAD THE B REGISTER WITH AAAAAAAA INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF3FOBOFFF COMPARE THE B REGISTER TO THE A REGISTER BRANCH TO MAJOR 21 MINOR 61 ON NO-GO	MEM EN #7
	5 F43NGG0	G FAULT IN MEMORY CONTROL- STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON INDICATORS DISPLAY REPLACE ASSEMBLIES NO.GO 1525252525 1A1A3A(7.8)	MEMORY EN #8
21 50		SPARE	IMV061 S@1
21 51	3 F41.NN	FAULT IN MEMORY CONTROL- STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	MEMORY EN #5

SE	стю	NII. SEL	F-TEST PROGRA	M (CONT)	
	ST O.	DECISION LEVEL	TEST/FAULT NUMBER	SELF-TEST PROGRAM	REMARKS
				INDICATORSDISPLAYREPLACE ASSEMBLIESNO.GO15252525251A1A3A(3*8*19*20)	
21 21	52 53			TEST FOR ACTIVE PE IN NCU CLOCK MODE AND MEMORY EN #6 SET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST NCU CLOCK MODE (GTC003*) SFRIALLY LOAD THE B REGISTER WITH AAAAAAAA INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF3F070FFF COMPARE THE B REGISTER TO THE A REGISTER BRANCH TO MAJOR 21 MINOR 55 ON NO-GO BRAMCH TO MAJOD 21 MINOR 63	ACTIVATE BKFO46* ANO IK4037 MEN EN #6
21	54			SPARE	
21 21	55 56	5	T43.NGNN	ATTEMPT SET OF "CLOCK CONTROL FF ENABLE CONTINUOS HIGH LEVEL ON GTCOO1* READ S COMPARE MISCELLANEOUS WORD I WITH AOOOOOC LOGICALLY 'AND' C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS BRANCH TO MAJOR 21 MINOR 57 ON NO-GO	GTCOO1* INACTIVE
		6	T43.NGNNG	RESET GTCOO1* WITH RCNU ENABLE CONTROLI.EO TIMING PULSE INTERVAL 10 ON GTCOOI* REAO & COMPARE MISCELLANEOUS WORD I WITH A LOGICALLY *AND' C REGISTER AND AOOOOOC - RESULT IN B & : REGISTER BRANCH TO MAJOR 21 MINOR 58 ON NO-GO	
		7	F43.NGNNGG	FAULT IN BKBOII STOP TAPE, DISPLAY C REGISTER NO-GO LIGHT ON	
				INDICATORSDISPLAYREPLACE ASSEMBLIESNO.GOBLANK1A1A3A(7*14*16*20*231)	
21	57	6	F43.NG.NNN	FAULT IN KMVO1LACTIVE STOP TAPE, OISPLAY C REGISTER, NO-GO LIGHT ON	
				INDICATORSDISPLAYREPLACE ASSEMBLIESNO.GO3001A1A3A(1*2*3*6*8)	
21	58	7	F43.NGNNGN	BBK031* INACTIVE STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	

-	ST 0.	DECISION	TEST/FAULT NUMBER		ę	SELF-TEST PROGRAM		REMARKS
	-			NO.GO	DISPLAY 300	REPLACE ASSEMBLIES 1A1A3A(4*7)		
21 21 21 21	59 60 61 62			SPARE SPARE SPARE SPARE				
21	63	1	TI4 T43.NGNG			LE- DRIVERS ALL INACTIVE		
21	64		143.NGNG	LOAD A REGISTER V SET INHIBIT INCF (GTC003*1 ENABLE CONTIN INITIATE SELF TE COMPARE THE E BRANCH TO MAJ ENABLE LOW LE	WITH AFFFFFF REMENT CP FLA UOUS HIGH LEV EST MODE 1-RE REGISTER TO IOR 21 MINOR 66 VEL ON GTCOO NCREMENT CP	G & ENABLE SELF TEST NCU CLOCK MODE EL ON GTCOO1* FAIN PREVIOUS BIT PATTERN IN SELF TEST F A ON NO-SO * FLAG & ENABLE SELF TEST CIU :LOCK MODE		١
21	65			SPARE				
21 21	66 67	2	T44.N	CHECK FOR ROM -> LOAD A REGISTER V INITIATE SELF TE COMPARE THE E BRANCH TO MAJ	WITH AOOOOOC EST MODE I-RET 3 REGISTER TO 2	O AIN PREVIOUS BIT PATTERN IN SELF TEST R A	E NOTHING AC	CTIVE
		3	F44.NS	COMPARE THE E	EST MODE 1-RE B REGISTER TO 2	TAIN PREVIOUS BIT PATTERN IN SELF TEST F	REG.	

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ITESTICECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARSS
TESTICECISION   TEST/FAULT	JEC TEST PROVING	
I NO.I LEVEL I NUMBER I		<b>L</b>

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INDICATORS	I DISPLAY IREPLACE_ASSEMBLIES
NO_GO	1_17000000012A1A2A18
NO_GO	<u>1 776000012A1A2A18</u>
NO_GO	<u>117740012A1A2A18</u>
NO_GO	<u>137712A1A2A18</u>
NO_GO	<u>1 10000000012A1A2A25</u>
NO_GO	<u>1 40000000124142425</u>
NO_GO	<u>1 20000000012A1A2A25</u>
NO_GO	<u>  10000000 24142425</u>
NO_GO	<u>1400000012A1A2A24</u>
NO_GO	_1200000012A1A2A24
NO_GO	<u>1 1000000012A1A2A24</u>
100_60	_1400000012A1A2A24
NO_GO	_L200000012A1A2A24
IND_60	_1100000012A1A2A24
NO_GO	<u>140000012A1A2A23</u>
NO_GO	<u>120000012A1A2A23</u>
I NO_GO	_ <u>10000012A1A2A23</u>
NO_GO	<u>140000124142423</u>
I <u>NO_GO</u>	<u>12000012A1A2A23</u>
NO_GO	_11000012A1A2A23
INO_GO	<u>400012A1A2A22</u>
NO_GO	_1200012A1A2A22
I <u>NO_GO</u>	_1100012A1A2A22
1 <u>NO_GO</u>	_140012 <b>&amp;1</b> &2 <b>&amp;</b> 22
ND_GO	_120012A1A2A22
I <u>NO_GQ</u>	_110012A1A2A22
IND_GO	_I4012A1A2A21
I NO_GO	_12012A1A2A21
1 NO_GO	_I1012A1A2A21
1 NO_GC	<u> </u>
NO_GO	<u>1</u> 21241A2A21
1 NO_GO	112A1A2A21

21 68 21 69	3	T44. NN	CHECK FOR SINGLE BIT FAULT Logically 'And' C register and AAAAAAAA - result in B & C register	
			BRANCH TO MAJOP 21 MINOR 70 ON NO-30 Branch to Major 21 minor 72	

21 70 21 71	4	T44.NNN	CHECK FURTHER FOR SINGLE BIT FAULT Initiate self test mode 1-retain previous bit pattern in self test reg.
			COMPARE THE B REGISTER TO A
			LOGICALLY 'AND' C REGISTER AND 55555555 - RESULT IN B & C REGISTER
			BRANCH TO MAJOR 21 MINOR 73 ON NO-SO

5 T44.NNNG CHECK EXMW REC EN INITIATE SELF TEST MODE 1-RETAIN PREVIOUS BIT PATTERN IN SELF TEST REG. COMPARE THE B REGISTER TO A00003 BRANCH TO MAJOR 21 MINOR 72 ON NO-GO

TESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS I
I NO.I LEVEL I NUMBER I		
بجري عب عم حم عم في عم النظرة فالتلك ومن في عالم من يا عب شكالا في ع	· · · · · · · · · · · · · · · · · · ·	

6 F44-NNNGG FAULT IN EXMW REC EN S@1

.

STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON

1 1401047000	1 01001 AV 1	BEPLACE ASSEMBLIES
- TUCTPATHR?		KEPLACE ASSEMBLIES
[NO_GO	I BLANK I	1 41 44 420
	باسميد من الألبان كالكم معالم عدم	4 <u>949194¥====================</u>

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21 72 6 F44.NNNGN F44.NNG

FAULT IN SINGLE BIT OF INPUT MUX OR RIM INITIATE SELF FEST MODE 1-RETAIN PREVIOUS BIT PATTERN IN SELF TEST RES. Compare the B register to a Stop Tape, Display C register, NO-GO Light on

		REPLACE_ASSEMBLIES
NO GO	1000000000	1A1A4A(11,12)
-	t 1	2A1A1A16
		2 A1 A2 A (19, 25)
NO GO	1 400000000	1A1A4A(11,12)
	1 (	2A1A1A16
		12A142A(19.25)
NO GO	200000000	1A1A4A(10,12)
		2 AI AI AI 6
		12A1A2A(19.25)
NO GO	100000000	1A1A4A(10,12)
		ZALAĽAĽ6
		[2A1A2A419+25]
NO 30		1A1A4A(10,12)
		2ATALA16
		2A1A2A419.24)
NO GO		1 A1 A4A (9;12)
		2A1A1A16
		2A1A2A(19+24)
NO GO	• • • • • •	1A1A4A(9,12)
		2A1A1A16
		241424(19.24)
NO 60		1A1A4A(9,12)
		24141416
		2A1A2A(19.24)
NO GO		141444(8,12)
		24141416
		[2A1A2A(19.24)
NO GO		1A1A4A(8,12)
		2 A1 A1 A16
		241424119.241
NO GO		1A1A4Af8, 12) -
		2 A1 A1 A1 6
		12A1A2A(19.23)
NO GO		1A1A4A(7, 12)
		2A1A1A16
		12A1A2A(19+23) JED ON FOLLOWING PAGE

ITESTICECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS I
NO.1 LEVEL 1 NUMBER 1		
	TABLE_CONTINUED_FROM_PRECEEDING_PAGE	
	IND GD   100000/1A1A4A(6,7)	<sub>1</sub>
	12A1A1A15	
	[[2A1A2A(16.23)	
	IND GD   40000[1A1A4A(6,7) 1   2A1A1A15	

NO GO	40000[LALA4A(0; //
	2A1A1A15
	12A1A2A(16.23)
NO GO	200001141444(5,6)
	2A1A1A15
	1 1 1 1 1 2 1 1 2 1 1 2 2 1 1 2 3 1
NO GO	1000011A1A4A(5,6)
	[ [2A1A1A15
	112A1A2A(16+23)
NO GO	1 4000   1 A 1 A 4 A ( 4 + 6 )
	1 12A1A1A15
	12A1A2A(22.26)
NO GO	2000/1A1A4A(4,6)
	124141415
	[] 2A142A(22,26)
NO GO	1 1000/141444(4,6)
	12 A1 A2 A (22,26)
NO GO	$\frac{1}{1} \qquad 400 1A1A4A(3, 6)$
NU GO	
	<u>12 A1 A2 A122 .261</u>
ND GO	200 1 1 1 4 4 4 ( 3, 6 )
	1 12 A1 A1 A1 5
	<u> </u>
NO GO	100/141444(3,6)
	2ALALA15
	I2A1A2A22
NO GO	40 1A1A4A(2,6)
	2A1A1A15
	<u>12A1A2A21</u>
NO GO	20 1A1A4A(2,6)
	[ [2A1A1A15
	124142421
NO GO	10/1A1A4A(2,6)
	2A1A1415
	12A1A2A21
NO GO	i 4/1A1A4A(1,6)
	1 24141415
	124142421
NO GO	2 1A1A4A(1,6)
	2A1A1A15
	12 A1 A2 A21
NO. CO.	
NO GO	1 1(1A1A4A(1,6)
	<u>12 A1 A2 A21</u>

-

21 73 5 21 74 T44.NNNN

TEST FOR FMB OR °JB FAULT INITIATE SELF TEST MODE 1-RETAIN PREVIOUS BIT PATTERN IN SELF TEST REG. COMPARE THE B PEGISTER TO AFFFFFF

	I TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
		BRANCH TO MAJOR 21 MINOR 76 ON NO-GO	
6	T44.NNNNG	ISOLATE BETWEEN FMB AND PJB INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 1FBFFF0FFF Compare the B register to A Branch to Majop 21 Minor 75 on NO-30	EN LOAD XMB
7	F44.NNNNGG	FAULT IN FMB REC EN Stop Tape, Display C register, ND-60 Light.ON	
		IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIES	1
75 7	F44.NNNNGN	FAULT IN PJB REC EN STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES	
76 6	F44.NNNNN	SET UP FAULT BIT PATTERN TO ISOLATE FAULT INITIATE SELF TEST MODE 1-RETAIN PREVIOUS BIT PATTERN IN SELF TEST REG COMPARE THE B REGISTER TO A STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	•
		I_INDICATORSI_DISPLAYIREPLACE_ASSEMBLIES	1
			I MA EN
		11A1A4A15	.1
			I PARTIAL MA EN
		ll_l_l_l_l_l_l_l_l_l_l_l_l_l_l_l_	I PARTIAL MA EN
		I IAIA4AI5 INO_GOI776011A1A4AI7 INO_GOI1770090FIA1A4A17 INO_GOI177400000011A1A4A17 INO_GOI_1774000000011A1A4A19	   PARTIAL MA EN   PARTIAL MA EN   TOTAL WD3 EN   PARTIAL WD3 EN
		International         International	I PARTIAL MA EN I PARTIAL MA EN I TOTAL WD3 EN I PARTIAL WD3 EN I PARTIAL WD3 EN
		Intervention         Intervention	I PARTIAL MA EN I PARTIAL MA EN I TOTAL WD3 EN I PARTIAL WD3 EN I PARTIAL WD3 EN I DISC DUT EN
		Image:	   PARTIAL MA EN   PARTIAL MA EN   TOTAL WD3 EN   PARTIAL WD3 EN   PARTIAL WD3 EN   DISC DUT EN   TOTAL MTW1 EN
		$\begin{tabular}{ c c c c c c c c c c c c c c c c c c c$	I PARTIAL MA EN I PARTIAL MA EN I TOTAL WD3 EN I PARTIAL WD3 EN I PARTIAL WD3 EN I DISC DUT EN I TOTAL MTW1 EN I PARTIAL MTW1 EN
		Image:	PARTIAL MA EN   PARTIAL MA EN   TOTAL WD3 EN   PARTIAL WD3 EN   PARTIAL WD3 EN   DISC OUT EN   TOTAL MTW1 EN   PARTIAL MTW1 EN   PARTIAL MTW1 EN
		$\begin{tabular}{ c c c c c c c c c c c c c c c c c c c$	I PARTIAL MA EN I PARTIAL MA EN I TOTAL WD3 EN I PARTIAL WD3 EN I PARTIAL WD3 EN I DISC DUT EN I TOTAL MTW1 EN I PARTIAL MTW1 EN
77		Image:	I PARTIAL MA EN PARTIAL MA EN TOTAL WD3 EN PARTIAL WD3 EN PARTIAL WD3 EN DISC DUT EN TOTAL MTW1 EN PARTIAL MTW1 EN PARTIAL MTW1 EN

 21 79 1
 T45
 TEST FOR ACTIVE RECEIVER, ALL DRIVERS ACTIVE

 21 80
 LOAD A REGISTER WITH AFFFFFF

 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH FFBFFFBFFF
 ALL DRIVERS ACTIVE

 COMPARE THE B REGISTER TO A
 BRANCH TO MAJOR 21 MINOR 82 ON NO-GO

	ECISION	TEST/FAULT	 	SELF-TEST PROGRAM	REMARKS
			BRANCH TO MAJOR 21 MIN	OR 98	
B1			SP ARE		
82 83	2	T45.N	CHECK RECEIVERS DRIVEN B LOAD A REGISTER WITH A Initiate self test mod Compare the B register Branch to Major 21 Min Branch to Major 21 Min	FFFFFFF E 1-LOAD SELF TEST REGISTER WITH BFBFFF0FFF TO A IOR 84 ON NO-GO	EN LOAD WOL
84	3	F44.NN	FAULT IN NAD RECEIVER STOP TAPE, DISPLAY C R	EGISTER, NO-GO LIGHT ON	
			INDICATORS	<u>     DISPLAY 1 REPLACE ASSEMBLIES</u> 17777777711ALA3A(19,21,24)     11A1A4A(16,19)	TOTAL NAD EN
			INO_60	1_1777000000114144416	I PARTIAL WAD EN
			NO_GO	1 77700011A1A4A16	PARTIAL NAD EN
			NO_60	<u>1</u> 77711A1A4A16	PARTIAL NAD EN
			I NO_GO	<u>1 1000000000114145411</u> 1 400000000114145411	SINGLE EN INPUT SƏL
				1 20000000114144410	SINGLE EN INPUT SOL
			INO_GO	1 10000000114144410	I SINGLE EN INPUT SOL
			NO_GO	1	SINGLE EN INPUT SO1
					SINGLE EN INPUT SOL
			1 NO_GO	<u>1 10000000114144409</u>	SINGLE EN INPUT SAL
			NO_GO		SINGLE EN INPUT SOL
			NO_GC	1 1000000114144408	SINGLE EN INPUT S21
			INO_GO	1 400000114144408	SINGLE EN ENPUT SOL
			I <u>NO_60</u>	1200000114145407	SINGLE EN INPUT SOL
			IND_GD	<u>1 10000041A1A4A07</u>	SINGLE EN INPUT Sal
			(ND_GO	<u>1 4000011A1A4A07</u>	SINGLE EN INPUT SO1
			I NO_GO	1 2000011A1A4A05 1 1000011A1A4A05	I SINGLE EN INPUT SƏ1 I SINGLE EN INPUT SƏ1
					I SINGLE EN INPUT SOI
				1 2000/14144404	SINGLE EN INPUT SOL
				1 100011A1A4A04	I SINGLE EN INPUT SAL
			1 <u>N0_60</u>	1 400114144403	I SINGLE EN INPUT SOL
			IND_GD	120011A1A4A03	I SINGLE EN INPUT SAL
			INO_GO	10011414403	SINGLE EN INPUT SOL
			1 NO_GO	<u>4011A1A4A02</u>	SINGLE EN INPUT SAL
			IND_GD	12011A1A4A02	SINGLE EN INPUT SOL

TEST CECISION	I TEST/FAULT	I SELF-TEST PROGRAM	REMARKS
		IABLE_CONTINUED_FROM_PRECEEDING_PAGE         IND_GD       411A1A4A01         IND_GO       211A1A4A01         IND_GO       1	I SINGLE EN INPUT SOL I SINGLE EN INPUT SOL I SINGLE EN INPUT SOL
1853 186	T4 5. NG	CHECK RECEIVERS DRIVEN BY CM & QTD LOAD A REGISTER WITH AFFFFFF INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 4FBFFF0FFF COMPARE THE B REGISTER TO A BRANCH TO MAJOR 21 MINOR 87 ON NO-GO BRANCH TO MAJOP 21 MINOR 88	EN LOAD QTM & QTD
21874	F45.NGN	IND_GQ       I       2000000011A1A4A10         IND_GQ       I       10000000011A1A4A10         IND_GQ       I       4000000011A1A4A10         IND_GQ       I       2000000011A1A4A09         IND_GQ       I       1000000011A1A4A09         IND_GQ       I       1000000011A1A4A09         IND_GQ       I       200000011A1A4A09         IND_GQ       I       200000011A1A4A09         IND_GQ       I       200000011A1A4A09         IND_GQ       I       200000011A1A4A09         IND_GQ       I       20011A1A4A03         IND_GQ       I       20011A1A4A03	I JCM EN SINGLE EN INPUT SOJ SINGLE EN INPUT SOJ SINGLF EN INPUT SOJ
21884 2189	745. NGG	CHECK RECEIVERS DRIVEN BY MB LOAD A REGISTER WITH AFFFFFFF INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 2FBFFF0FFF Compare the B register to A Branch to Major 21 Minor 90 on NO-GO Branch to Major 21 Minor 91	EN LOAD QTB
1905	F45.NG3N	FAULT IN JEB OR WD1 RECEIVER STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I INDICATORS I DISPLAY I SEPLACE ASSEMBLIES NO GO I 17777777711A1A3A(19,21)	I TOTAL #D1 OR JEB EN

		an a
INO GO	177777777711A1A3A(19,21)	I TOTAL AD1 OR JE
1	ii1A1A4A(15,19,20)	1
IND GO	1777760000 1A1A3A16	I JCP EN
1		f
	TABLE CONTINUED ON FOLLOWING PAGE	

ITESTICECISION I TEST/FAULT I	SELF-TEST PROGRAM	1	REMARKS	1
I_NO.L_LEVEL_L_NUMBERL	ذ ف منه	L	<b></b>	İ.

	<u>1_177000000011A1A4A(17+20)</u>	
	l7760000L1A1A4A17	
NO_GO	<u>1740011A1A4A(15,17)</u>	JCI EN
NO_GO	<u>l37011A1A4A(15+16)</u>	
<u>NO_GO</u>	<u>i711A1A4A(15,16)</u>	
NO_GO	1774000011A1A4A20	PARTIAL JEB EN
NO_GC	<u>13760011A1A4A20</u>	PARTIAL JEB EN
NO_GO		
NO_GL	<u>i_1000000000011A1A4A11</u>	SINGLE EN INPUT Sal
NO_GO	I_40000000C[1A1A4A11	SINGLE EN INPUT SO1
NO_GO	I20000000011A1A4A10	
NO_GO	i_10000000011A1A4A10	SINGLE EN INPUT SOL
NO_GO	L 400000011A1A4A10	I SINGLE EN INPUT SOL
NO_GO	12000000011A1A4A09	SINGLE EN INPUT SOL
NO_GO	i 100000011A1A4A09	SINGLE EN INPUT Sal
NO_GC	1 400000011A1A4A09	
NO_GO		SINGLE EN INPUT SOL
NO GO	1 200000011A1A4A08	I SINGLE EN INPUT Sal
NO_GO		
NO GO	L 40000011A1A4A08	I SINGLE EN INPUT SOL
NO_GO	1 20000011A1A4A07	I SINGLE EN INPUT SOL
NO_GO	10000011A1A4A07	SINGLE EN INPUT SOL
NO_GO		
NO_GO		
NO_30		
	4000114144404	
NO_GO		
NO GO	1000114144404	
	400118184803	
NO_GO	200/14144403	
NO GO		
NO_SO		
NO_GO		
NO_GO		
NO_GO	4118184801	SINGLE EN INPUT SOI
NO_GO	211 41 44 401	
NO_GO		SINGLE EN INPUT SOL

21 91 21 92	5	T45.NGGG	CHECK RECEIVERS DRIVEN BY XMB DRIVERS LOAD A REGISTER WITH AFFFFFF INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 1FBFFF0FFF COMPARE THE B REGISTER TO A	EN LOAD XMB
			BRANCH TO MAJOR 21 MINOR 93 ON NO-GO BRANCH TO MAJOR 21 MINOR 94	

21 93 6 F45.NGGGN FAULT IN XMB RECEIVER STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON

TEST CECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS I
I_NO.I_ LEVEL I NUMBER I		i i i
I_NO_1_LEVEL_1NUMBER1	***************************************	

I INDICATORS	LDISPLAY	
IND_GO	L_177777777711A1A4A(16,18)	
NO GO	1000000000114144412	I SINGLE XMB EN INPUT S21
NO GO	1 XXX00000011A1A4A12	SINGLE XMB EN INPUT SOL
NO_GO	40000011A1A4A12	SINGLE XMP EN INPUT SOL
IND_GD	20000011A1A4A12	I SINGLE XMB EN INPUT SØ1
NO GO	10000011A1A4A06	SINGLE XMB EN INPUT SOL
		SINGLE XMB EN INPUT SUI

 21 94 6
 T45.NGGGG
 CHECK RECEIVEP DRIVEN BY QJD

 21 95
 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFF8FFF
 EN LOAD QJD

 COMPARE THE B PEGISTER TO A
 BRANCH TO MAJOR 21 MINOR 96 ON NO-GO

7 T45-NGGGGG THIS IS NOT A NORMAL FAULT LOCATION STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON

		REPLACE_ASSEMBLIES	
1 <u>NO_GO</u>	BLANK	_IPROCEED_PER_PARAGRAPH_3=13I	

21 96 7 F45.NGGGGN FAULT IN SINGLE RIT OF EXT MEM RECEIVER STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON

	I DISPLAY I REPLACE ASS		
1NO_GO	i411A1A4A01	SINGLE EN IN	IPUT Sal
	2011A1A4A02		
NO_GO	14011A1A4A02	SINGLE EN IN	IPUT Sal

- 21 97 SPARE
- 2198ENABLE VERTICAL PARITY CHECK2199END OF MAJOR TEST

107

TESTI CECISIO	N   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
	*******	***********************	******
	- + + ++++++++++++++++++++++++++++++++	INTERNAL MULTIPLEXERS TEST	* * *
2 00		INITIALIZE	
.2 00		DEFINE SELF TEST TAPE BRANCH TO MAJOP 22 MINOR 3	
22 01 22 02		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
2 03 2	T4 8	TEST A REG -> RDM -> RIM -> B REG, DATA = AFFFFFFF	
2 04		SERIALLY LOAD THE B REGISTER WITH A Load a register with Affffff	PREVIOUS TEST = (21)T49
		INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFF0F7F Compare the B register to the A register Branch to Major 22 minor 6 on NO-GO Branch to Major 22 minor 17	ROM -> RIM
2 05		SPARE	
22 06 2 22 07	748.N	CHECK FOR PARTIAL ROM->RIM EN FAULT Compare the B register to Affffoo Branch to Major 22 Minor 10 on No-So Branch to Major 22 Minor 14	
22 08		SPARE	
22 09		SP AR E	
22 10 4	F48.NN	SINGLE BIT ROM -> RIM INACTIVE LOAD A REGISTER WITH AFFFFFF INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFF0F7F Compare The B register to the A register STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT DN	ROM -> RIM

TESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS I
I NO.I LEVEL I NUMBER I		
	• •	

INDICATORS		BEPLACE ASSEMBLIES	
NO GO	200000000000	2A1A1A16 1	
	_11	24142401	
NO_GO	_L_17000000001	24141416	BRES PE
NO_GO	_1740000001	24141416	BREG PE
NO GO			BREG PE
NO_GD	1700001	24141415	BREG PE
NO_GO	74001	2A1A1A15	BREG PE
NO GO	1360]	24141415	BREG PE
NO_GO		24141415	BREG PE
NO GO	1000000000	24141416	
		24142425	
NO GO	I X00000000		
I		241424(19,25)	
NO GO	XX000000		
İ		241424(19.24)	
PNO GO	• • • • • • • • •	2A1A1A16	
		2A1A2A(19+24)	
NO GO		2A1A1A16	
		2A1A2A(19.24)	
NO GO		24141415	
l		2 <u>A1A2A(23.16)</u>	
NO GO		24141415	
		2A1A2A(23.16)	
NO GO		2A1A1A15	
<u></u>		2A1A2A(22+26)	
NO GO		2A1A1A15	
		241424(22+26)	
NO GO	•	2 A1 A1 A1 5	
		24142422	l
INO GO		2 A1 A1 A1 5	
		24142422	
NO GO ,	•	24141415	l
t		2 A1 A2 A21	

22 11 22 12

SP AR E SP AR E

22 13 22 14 4 F48.NG FAULT IN ROM -> RIM EN STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON

TESTIDECISION		I SELF-TEST PROGRAM	I REMARKS
		I INDICATORS I DISPLAY I BEPLACE ASSEMBLIES	
22 15 22 16		SP ARE SP ARE	
22 17 1 22 18	Τ49	TEST A REG -> ROM -> RIM -> B REG, DATA = 50000000 SERIALLY LOAD THE B REGISTER WITH AFFFFFFF LOAD A REGISTER WITH 50000000 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFF0F7F COMPARE THE B REGISTER TO THE A REGISTER BRANCH TO MAJOR 22 MINOR 20 ON NO-GO BRANCH TO MAJOR 22 MINOR 22	ROM -> RIM
22 19		SPARE	
22 20 3	F49.N	FAULT IN ROM -> PIM, BIT SƏl         STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON         I	BIT 31 INACTIVE
22 21		SPARE	
22 22 1 22 23	т50	TEST FOR FAULT IN EN B REG OR C REG -> ROM SERIALLY LOAD THE B REGISTER WITH AFFFFFF COMPARE THE B REGISTER TO F INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFF0F7F COMPARE THE B REGISTER TO THE A REGISTER BRANCH TO MAJOR 22 MINOR 25 ON NO-GO BRANCH TO MAJOR 22 MINOR 27	SET UP ALL ONES IN BIT 1 - 28 OF B & C REG RDM -> RIM

TEST DECISION	TEST/FAULT _INUMBEB	I SELF-TEST PROGRAM	I REMARKS
22 25 2	F50.N	FAULT IN B OR C -> ROM EN ACTIVE         STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON         I	
22 26		ING. GOIXX12A1A1A29I	
22 27 1 22 28	751	TEST B REG -> ROM -> RIM -> B REG, DATA = AFFFFFF SERIALLY LOAD THE B REGISTER WITH AFFFFFF LOAD A REGISTER WITH A0000000 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFF077F COMPARE THE B REGISTER TO AFFFFFFF BRANCH TO MAJOR 22 MINOR 32 ON NO-GO BRANCH TO MAJOR 22 MINOR 38	BREG->ROM, ROM->RIM
22 29 22 30 22 31		SPARE SPARE SPARE	
22 32 2	F51.N	FAULT IN B REG CHAN OF ROM STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON         INDICATORS       I DISPLAY         IND.GO       I 1777777712A1A1A1A(7.19)         INO.GO       I 17000000012A1A1A19         INO.GO       I 17740012A1A1A19         INO.GO       I 17740000000012A1A1A19         INO.GO       I 1700000000012A1A1A19         INO.GO       I X00000000012A1A1A19	

L XX000012A1A1A25 TABLE CONTINUED ON FOLLOWING PAGE

ESTIDECISI	ON   TEST/FAULT	SELF-TEST PROGRAM	I RENARKS
		TABLE CONTINUED FROM PRECEEDING PAGE	
		1 MO GO 1 XX0012A1A1A28	
		1 <u>80-601XX12A1A1A29</u>	_1
33		SPARE	
34		SPARE	
35 36		SPARE SPARE	
37		SP ARE	
38 1	T52	TEST BREG -> ROM -> RIM -> BREG, DATA = 50000000	
39		LOAD A REGISTER WITH 50000000 Initiate self test mode 1-load self test register with ofbfffof7f	ROM->RIM
		LOAD A REGISTER WITH SFFFFFF	
		INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH DFBFFF077F Compare the B register to 5	BREG->ROM, ROM->RIM
		BRANCH TO MAJOF 22 MINOR 40 ON NO-GO	
		BRANCH TO MAJOR 22 MINOR 47	
40 2	T52.N	TEST FOR NO INH OF AREG -> ROM	
2 41		COMPARE THE B REGISTER TO 5FFFFFF Brancy to major 22 minor 42 on NO-Go	
3	F52.NG	FAULT IN INH DF AREG -> RDM	
		ENABLE VERTICAL PARITY CHECK	
		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		I INDICATORS I DISPLAY I REPLACE ASSEMBLIES	-
		1NO.GO1BLANK12A1A1A19	ī.
42 3	F52.NN	FAULT IN BREG -> ROM, BIT \$21, OR PARTIAL AREG -> ROM EN \$21	
		COMPARE THE B PEGISTER TO 5	SET UP FAULT BIT
		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		I INDICATORS I DI SPLAY I BEPLACE ASSEMBLIES	_!
			-!
		NO.GO I XX00000001241414(16.21)	
		NO_60	_1
		NO_GO 2000001241414(16,25)	<u>_</u> !
			-}
		NO_GOIX000012 A1 A1 A(15,25)	
		TABLE CONTINUED ON FOLLOWING PAGE	·•• •

TESTIDECISION	TEST/FAULT	I SELF-TEST PROGRAM	REMARKS
		TABLE CONTINUED EBOM PRECEEDING PAGE         INO_GO       IXXI2AIAIA(15:29)         INO_GO       I 170000000012AIAIA19         INO_GO       I 17000000012AIAIA19         INO_GO       I 17740012AIAIA19         INO_GO       I 37712AIAIA19	EN AREG->ROM SƏ1 EN ARE3->ROM SƏ1 EN AREG->ROM SƏ1 EN AREG->ROM SƏ1
22 43 22 44 22 45 22 46		SPARE SPARE SPARE S≥ARE	
22 47 1 22 48	T 5 3	TEST C REG -> ROM -> RIM -> B REG, DATA = AFFFFFF SERIALLY LOAD THE B REGISTER WITH AAAAAAAA COMPARE THE B REGISTER TO 0555555 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFF0B7F COMPARE THE B REGISTER TO AFFFFFFF BRANCH TG MAJOR 22 MINOR 52 ON ND-GO BRANCH TO MAJOP 22 MINOR 55	C = AFFFFFF C REG -> ROM, RDM->RIM
22 49 22 50 22 51		SP AR F SP AR E SP AR E	
2 52 2	F53.N	FAULT IN C REG CHAN OF ROM STOP TAPE, CISPLAY C REGISTER, ND-GO LIGHT ON         INDIC/IORSI_DISPLAY_I	
22 53 22 54		SP AR E SP AR E	
22 55 1 22 56	T54	TEST C REG -> ROM -> RIM -> B REG, DATA = 50000000 Serially load the B register with AAAAAAAA Compare the P pegister to faaaaaaa Load A register with 5ffffff	C-REG = 5000000

TESTICE		TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
			INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFFOB7F Compare the B register to 5 Branch to major 22 minor 57 on NO-go Branch to major 22 minor 64	C REG -> ROM, ROM->RIM
22 57 22 58	2	T54.N	TEST FOR NO INH OF AREG -> ROM Compare the B register to 5FFFFFF Branch to Major 22 Minor 60 on NO-GO	
	3	F54.NG	FAULT IN INH OF AREG -> ROM ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATOBSI_DISPLAYIBEPLACE_ASSEMBLIESI IND_GOIBLANKI2A1A1A19I	
22 59			SPARE	
22 60 22 61 22 62	3	F54.NN	FAULT IN C REG -> ROM, BIT SƏL COMPARE THE R REGISTER TO 5 STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON SPARE COADE	SET UP FAULT BIT
22 63			SPARE SPARE	
			INDICATORS       I       DISPLAY       I       REPLACE ASSEMBLIES       I         IND.GQ       IX00000000012A1A1A(B.20)       I       IX0.2000000012A1A1A(B.21)       I         IND.GQ       I       XX000000012A1A1A(B.21)       I       I         IND.GQ       I       XX00000012A1A1A(B.21)       I         IND.GQ       I       20000012A1A1A(B.25)       I         IND.GQ       I       20000012A1A1A(B.25)       I         IND.GQ       I       10000012A1A1A(B.25)       I         IND.GQ       I       10000012A1A1A(B.25)       I         IND.GQ       I       XX000012A1A1A(B.25)       I         IND.GQ       I       XX00012A1A1A(B.25)       I         IND.GQ       I       XX00012A1A1A(B.25)       I         IND.GQ       I       XX00012A1A1A(B.25)       I         IND.GQ       I       XX0012A1A1A(B.28)       I         IND.GQ       I       XX0012A1A1A(B.28)       I	

22 64	1	T55	TEST A REG -> ROM -> DSPL -> IN MUX -> RIM + MSHD DSPL -> B REG, DATA = AFFFFFFF	
22 65			LOAD A REGISTER WITH AFFFFFF INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB77F0FBF	RDM 4MS
			COMPARE THE B REGISTER TO THE A REGISTER Branch to major 22 minor 70 on ND-Go Branch to major 22 minor 76	-113

RDM -> DSPL, JSPL -> IN MUY, 4MSB DSPL -> RIM

TESTIDECISION	I TEST/FAULT			SELF-TEST PROGRAM	REMARKS
2 66	<u></u>	SPARE			# <b>##8</b> 1000
67		SPARE			
2 69		SP AR E SP AR E			
• • •		0			
270 2	F55.N			OR 4MSB DSPL -> RIM, BIT S@O Register, NO-go light on	
		STUP TAPE	DIS-LAT C	REGISTER, NU-GU LIGHT UN	
		1	INDICATORS	I DISPLAY I BEPLACE ASSEMBLIES	-1
		1 NC	GO	1777777777 1A1A2A21	EN DSPL -> IN MUX INACTIV
			)_GO	124000000000124142420	_1 AAX017 S@0
				11000000000012A1A2A20	-'   RIM BIT SƏ1
			1_GO	I_40000000012A1A2A25	I RIM BIT SOO
			1 60	1_200000000012A1A2A25	_ RIM BIT SƏ1
			<u>]_GO</u>	_1_10000000011A1A4A11	_t
			<u></u>	_140000000011A1A4A11	-!
			0_60		-1
			1_ <u>60</u>	<u>1 1000000011A1A4A10</u> 1 4000000011A1A4A10	_1 
			J GD		-
			)_G0	1 1000000011A1A4A09	
			)_60	4000000114144409	_1
			)_GQ	200000011A1A4A(8+12)	_!
			<u>]_GO</u>	<u>1 100000011A1A4A08</u>	-1
			<u>)_GO</u>		-!
			1_GO	i10000011A1A4A07	-!
			0.60		-
			J GO	1 20000114144405	_1
			1 60	1 10000114144405	<u>_1</u>
			0_60	40001141444(4+6)	-!
			0_60	1 2000/1 41 44 404	-!
			0_60	<u>1</u> <u>100011A1A4A04</u> 1 <u>40011A1A4A(3.6)</u>	-!
			0_60		-1
			0 60	1. 100114144403	
			0_GO	1 4011A1A4A(2.6)	_1
			0_60	20114144402	_!
			0_60	10114144402	_!
			0_60	41181848(1.6)	-!
			0 <u>G0</u> 0 G0	1211A1A4A01	
		(1)	<b>U</b>		
2 71		SP AR E			
2 72		SPARE			

24 16	37 AK C
22 73	SPARE
22 74	SPARE

22 75 SPARE

ITESTIDECISIC	DN I TEST/FAULT		SELF-TEST PROGRAM	I REMARKS
22 76 1 22 77	T56	LOAD A REGISTER WITH	DE 1-LOAD SELF TEST REGISTER WITH OFB77FOFBF R TO THE A REGISTER	ROM -> D\$PL, DSPL -> IN MUX, 4MSB DSPL -> RIM
		BRANCH TO MAJOR 22 MI		
22 78 22 79		SPARE SPARE .		
22 80 2	T56.N	FAULT IN DSPL CHAN OF I Stop Tape, Display C	N MUX OR RIM, BIT SƏ1 Register, ND-go light on	
		INCICATORS INC GO INC GO	1       DISPLAY       1       BEPLACE ASSEMBLIES         1360000000012A1A2A20       120000000012A1A2A20       120000000012A1A2A20         1200000000012A1A2A20       100000000012A1A2A20         120000000012A1A2A20       120000000012A1A2A20         120000000012A1A2A25       120000000012A1A2A25         120000000012A1A2A11       1         120000000011A1A4A11       1         1       4000000011A1A4A11         1       4000000011A1A4A11         1       20000000011A1A4A11         1       20000000011A1A4A11         1       2000000011A1A4A11         1       2000000011A1A4A11         1       2000000011A1A4A11         1       2000000011A1A4A01         1       2000000011A1A4A09         1       2000000011A1A4A09         1       200000012A1A1A08         1       200000012A1A1A08         1       200000011A1A4A08         1       200000011A1A4A08         1       200000011A1A4A08         1       20000011A1A4A08         1       20000011A1A4A08         1       20000011A1A4A08         1       20000011A1A4A08         1       20000011A1A4A08         1 </td <td>FYR549* SƏ1 FYR549* INPUT TO AAB313* S71 AA5215 SƏO RIM BIT SƏ1 RIM BIT SƏO RIM BIT SƏ1 RIM BIT SƏO</td>	FYR549* SƏ1 FYR549* INPUT TO AAB313* S71 AA5215 SƏO RIM BIT SƏ1 RIM BIT SƏO RIM BIT SƏ1 RIM BIT SƏO
22 81 22 82 22 83 22 84		SP ARE S <sup>D</sup> ARE SP ARE SP ARE		

22 85	1	T 5 7	TEST FOR SHORT ROM -> RIM -> B REG
22 86			LOAD A REGISTER WITH 88888888

TESTIDECISION   TEST/FAULT		I REMARKS
_	INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFFOF7F Compare the 8 register to 88888888 Branch to major 22 minor 90 on ND-Go	ROM -> RIM
	LOAD A REGISTE <sup>1</sup> with 44444444 Initiate Self Test Mode 1-Load self Test register with ofbfffof7f Compare the R register to 44444444 Branch to Majop 22 Minor 90 on ND-GD	RDM -> RIM
	LOAD A REGISTER WITH 22222222 Initiate Self test mode 1-load self test register with ofbfffof7f Compare the B register to 22222222 Branch to major 22 minor 90 on NO-Go	ROM -> RIM
	LOAD A REGISTER WITH 11111111 Initiate Self test mode 1-load self test register with ofbfffof7f Compare the B register to 11111111 Branch to major 22 Minor 90 on NO-GO	ROM -> RIM
	LOAD A REGISTER WITH 01240000 Initiate self test mode 1-Load self test register with ofbfffof7f Compare the B register to 01240000 Branch to majop 22 Minor 90 on NO-G0	ROM → RIM
	LOAD A REGISTEP WITH 48120000 Initiate Self Test mode 1-load self Test register with ofbfffof7f Compare The B register to 48120000 Branch to Major 22 Minor 90 on ND-G0	ROM -> RIM
	LOAD A REGISTER WITH 24810000 Initiate Self test mode 1-load self test register with ofbfff0f7f Compare the B register to 24810000 Branch to majop 22 minor 90 on ND-GD	R04 -> 3IM
	LOAD A REGISTEP WITH 12480000 Initiate self test mode 1-load self test register with ofbfffof7f Compare the B register to 12480000 Branch to major 22 minor 90 on ND-GO	ROM -> RIM
	LOAD A REGISTER WITH 00008124 Initiate self test mode 1-load self test register with ofbfffof7f Compare the B register to 00008124 Branch to major 22 Minor 90 on ND-G0	ROM -> RIM
	LOAD A REGISTER WITH 00004812 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFF0F7F Compare the B register to 00004812 Branch to Major 22 Minor 90 on ND-GD	RDM -> RĮM
	LOAD A REGISTER WITH 00002481 Initiate Self Test mode 1-load self test register with ofbfffof7f Compare the B register to 00002481 Branch to major 22 minor 90 on ND-GD	RDM -> RIM

	TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
		LOAD A REGISTER WITH 00001248 Initiate self test mode 1-load self test register with ofbfffof7f Compare the B register to 00001248 Branch to major 22 minor 90 on no-go	ROM -> RIM
		BRANCH TO MAJOR 22 MINOR 93	
2 87 2 88 2 89		SPARE SPARE SPARE	
2 90 2	F57.N	SHORT IN ROM -> RIM -> B REG STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		IND_GOIXXXXXXXXIHIGHER_LEVEL_OF_MAINIENANCEI	
2 91 2 92 2 93 2	T 5 8	TEST FOR SHORT DSPL -> IN MUX -> RIM	
94		LOAD A REGISTER WITH 888888888 Initiate Self test mode 1-load self test register with of877fof8f Compare the P register to 888888888 Branch to major 22 minor 96 on ND-GO	ROM -> DSPL, DSPL -> IN P 4MSB DSPL -> RIM
		LOAD A REGISTER WITH 44444444 Initiate self test mode 1-load self test register with ofb77fofbf	ROM -> DSPL+ DSPL -> IN 4MSB DSPL -> RIM
		COMPARE THE B REGISTER TO 44444444 Branch to major 22 minor 96 on No-Go	
		LOAD A REGISTER WITH 22222222 Initiate self test mode 1-load self test register with ofb77f0f8f	ROM -> DSPL, DSPL -> IN (
		COMPARE THE R REGISTER TO 2222222 Branch to major 22 minor 96 on ND-60	4MSB DSPL -> RIM
		LOAD A REGISTEP WITH 11111111 Initiate self test mode 1-load self test register with OFB77FOFBF	ROM -> DSPL, DSPL -> IN / 4MSB DSPL -> RIM
		COMPARE THE B REGISTER TO 1111111 Branch to Major 22 Minor 96 on NO-GO	
		LOAD A REGISTER WITH 81240000 Initiate Self test mode 1-ldad self test register with ofb77f0fbf	ROM -> DSPL, DSPL -> IN I

ITESTIDECISION   TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
	COMPARE THE B PEGISTER TO 81240000 Branch to Major 22 minor 96 on ND-GD	
	LOAD A REGISTER WITH 48120000 Initiate self test mode 1-load self test register with ofb77fofbf	ROM -> DSPL, DSPL -> IN MUY 4MSB DSPL -> RIM
	COMPARE THE B PEGISTER TO 48120000 Branch to Major 22 Minor 96 On NO-GO	
	LOAD A REGISTER WITH 24810000 Initiate self test mode 1-load self test register with ofb77f0fbf	ROM -> DSPL, DSPL -> IN MUX 4MSB DSPL -> RIM
	COMPARE THE B REGISTER TO 24810000 Branch to Major 22 Minor 96 on ND-Go	HOU DOFE - 7 KIN
	LOAD A REGISTER WITH 12480000 Initiate self test mode 1-load self test register with ofb77fof8f	ROM -> DSPL, DSPL -> IN MUX 4MSB DSPL -> RIM
	COMPARE THE B REGISTER TO 12480000 Branch to Major 22 Minor 96 ON NO-GO	4MSB USPL -> KIM
	LOAD A REGISTER WITH 00008124 Initiate self fest mode 1-load self test register with ofb77fofbf	ROM -> OSPL, DSPL -> IN MUX 4MSB DSPL -> RIM
	COMPARE THE B REGISTER TO 00008124 Branch to major 22 minor 96 DN ND-GO	4436 USPL -7 KIN
	LOAD A REGISTEP WITH 00004812 Initiate self test mode 1-load self test register with 0FB77F0F8F	ROM ~> DSPL, DSPL ~> IN MU; 4MSB DSPL -> RIM
	COMPARE THE B REGISTER TO 00004812 Branch to major 22 minor 96 on NO-GO	THOUSTE -7 KIN
	LOAD A RÉGISTE® WITH 00002481 Initiate self "est mode 1-load self test register with ofb77fofbf	ROM -> DSPL, DSPL -> IN MUX 4MSB DSPL -> RIM
	COMPARE THE B REGISTER TO 00002481 Branch to Majop 22 minor 96 on ND-GO	4130 03FL -7 KIN
	LOAD A REGISTER WITH 00001248 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 0FB77F0FBF	ROM -> DSPL, DSPL -> IN MUY 4MSB DSPL -> RIM
	COMPARE THE B REGISTER TO 00001248 Branch to majo? 22 minor 96 on NO-go	4M30 USPE -7 KIM
	BRANCH TO MAJOR 22 MINOR 98	
22 95	SPARE	
22 96 2 <b>F58</b> •F	SHORT IN IN MUX -> RIM, OR IN 4MSB OF RIM /	

22 96 2 FSB.F SHURI IN IN MOX -> RIM, DR IN 4MSB OF RIM ' STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON

شدر از مربو <sub>ا</sub> و من میں اور ورز کر میرود اور اور اور وال کا ک <sup>ر</sup> کر اور اور وال کر دور میں اور کر اور اور اور اور اور اور اور اور اور او		
ITESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS I
• • • • • • • • • • • • • • • • • • • •		
I_NO.I_LEVEL_LNUMBERI		······································

I_INDICATORS	DI SPLAY	.1 BEPLA	CE ASSEMBLIES	
NO GO		LEVEL	OF MAINTENANCE	

22 97 SPARE

22 98	ENABLE VERTICAL PARITY CHECK
22 99	END OF MAJOR TEST

120

TESTICEC	ISION   TEST/FAULT EveliNUMBER		REMARKS
	************ * * *	TEST SET CLOCK MODE AND NGU CLOCK CONTROL TESTS	**************** * *
3 00	********	INITIALIZE- NOT A TEST DEFINE SELF TEST TAPE BRANCH TO MAJOR 23 MINOR 3	
3012	F31.1	BPC638* SQ1 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIES IND_GOIBLANKIIAIAIA(21,23)	
3 02		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
3031 304	T60	CHECK STATE OF GTCOO1*. PREVIOUS TEST = (22)T58 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OF9FFFOFFF COMPARE THE 8 PEGISTER TO A LOGICALLY 'AND' C REGISTER AND A00000C - RESULT TN B & C REGISTER BRANCH TO MAJOR 23 MINOR 6 ON NO-GG BRANCH TO MAJOP 23 MINOR 20	MTW1 -> IN MUX No-go for gtcool* = 1
3 05		SPARE	
3062 307	T60.N	ATTEMPT RESET OF GTC00)* WITH INST STCL ENABLE LOW LEVEL ON GTC001* REAC & COMPARE MISCELLANEOUS WORD 1 WITH A LOGICALLY 'AND' C REGISTER AND A00000C - RESULT IN B & C REGISTER BRANCH TO MAJOR 23 MINOR 9 ON ND-GO	NO∽GD IF GTC003* =1
23 08 3	t60.N3	TEST TST1(MTW1 ->{NMX} INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OF9FFF0FFF COMPARE THE B REGISTER TO A LOGICALLY 'AND' C REGISTER AND A00000C - RESULT IN B & C REGISTER BRANCH TO MAJOR 23 MINOR 13 ON NO-GO BRANCH TO MAJOF 23 MINOR 20	MTW1->INMX
23 09 3	5 T60. NN	ATTEMPT RESET OF"CLOCK CONTROL FF"WITH RCNU, USES"DC CLOCK STOP"	

	ION   TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS I
23 10		SET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST NCJ CLOCK MODE (GTC003*) ENABLE CONTROLLED TIMING PULSE INTERVAL 10 DN GTC001* READ & COMPARE MISCELLANEOUS WORD 1 WITH A LOGICALLY 'AND' C REGISTER AND A00000C - RESULT IN B & C REGISTER BRANCH TO MAJOP 23 MINOR 14 ON ND-GD	NO-GO 1F GTC003* =1
23 11 4	T60.NNG	ATTEMPT RESET OF "CLK CONTROL FF" WITH EOP "STOP COMP CLK" ENABLE CONTINUOUS HIGH LEVEL ON GTCOOL* LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3E600 READ & COMPARE MISCELLANEOUS WORD 1 WITH A LOGICALLY 'AND' C REGISTER AND A00000C - RESULT IN B & C REGISTER LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A00000 BRANCH TO MAJOR 23 MINOR 12 ON NO-GO	SET UP EA =0371, I/O REC INACTIVE I/O REQ ACTIVE ND-GO IF GTC003* =1
5	F60.NNGG	FAULT IN STCL 167 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDIGATORSI_DISPLAYL	-1 1 BAD116* SƏI -1
23 12 5	F60.NNGN	CKB123 # INACTIVE STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON I_INFIGATORSIDISPLAYBEPLAGE_ASSEMBLIES IND_GO30011A1A3A(12,13)	- - 1
23 13 4	760.N3N	FAULT IN TSTI(MTW1->INMX) ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYI	 _    Fyr010* Sə1 _!
23 14 4 23 15	T60-NNN	ATTEMPT SET OF RESET COMPUTER FLAG ENABLE COMPUTER RESET (GTC000*) READ & COMPARE MISCELLANEOUS WORD 1 WITH A COMPARE THE P REGISTER TO A LOGICALLY 'AND' C REGISTER AND A0002 - RESULT IN B & C REGISTER BRANCH TO MAJOR 23 MINOR 18 ON NO-GO	ND-GO FJR GT2000* = 1
5	F60.NNNG	FAULT IN GTCOO1* -> MTW1 READ & COMPARE MISCELLANEOUS WORD 1 WITH A	

TESTIDECISION		I SELF-TEST PROGRAM	I REMARKS
		LOGICALLY 'AND' C REGISTER AND A00000C - RESULT IN B & C REGISTER STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDIGATORSI_DISPLAYIBEPLACE_ASSEMBLIESI IND GOI30011A1A3A02I IND_GOI20011A1A3A02I IND_GOI20011A1A3A03I	NO-GO IF GTC003* =1
3 16		SPARE	
3 17		SPARE	
318 5	F60.NNNN	FAULT IN RESET GTCOOI* TO 0, OR INST DECODE MATRIX STOP TAPE IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIESI INONEI_BLANKILAIA3AI6.7.12.13.221I STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIESI IND_GOIXXXXXXXXXIPROCEED_PER_PARAGRAPH_3-12DI	
3 19		SPARE	
3 20 1 3 21	T61 T60.NGG	CHECK STATE OF GTC001* IN NCU CLOCK MODE SET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST NCU CLOCK MODE (GTC003*)	
2	F61.1	FAULT LOC WITHIN TEST T61, NOT A PROGRAMMED STOP- NCU CLK MODE MAL	
1	T61(CONT)	INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OF9FFF0FFF COMPARE THE 8 REGISTER 10 A LOGICALLY 'AND' C REGISTER AND A00000C - RESULT IN B & C REGISTER BRANCH TO MAJOR 23 MINOR 24	MTW1 -> IN MUX NO-GO FOR GTC001* = 1

23 22 SPARE

K CONTROL FF" SƏL PLAY C REGISTER, NO-GQ LIGHT ON ATORS I DISPLAY L. BEPLAGE ASSEMBLIES
I30011A1A3A13.6.7.151I
. CONTROL FF" WITH RCPC TEST MODE 2-LOAD SELF TEST REGISTER WITH OF9FFF0FFF SET UP BIT PATTERN FDR FOLLOWING, MTW1->INMX
CUS HIGH LEVEL ON GTCOOI* Test mode 1-retain previous bit pattern in self test reg.
REGISTER TO 400000C • C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS NO-GD IF GTCOD1* = 0 • 23 Minor 27 on ND-GD IR 23 Minor 44
C LATCH MISCELLANEOUS WORD 1 WITH A OF C REGISTER AND AO1 - RESULT IN B & C REGISTER NO-GO IF GTCOO3* =1 OR 23 MINOR 39 ON NO-GO
. "OC CLK STOP" The B register with Affffff
TEST MODE 2-LOAD SELF TEST REGISTER WITH OFIFOBOFFF INH ALL MEM EXCEPT #7- KMA091, EN MTW1 -> IN C MEMORY MODE WITH ADDRESS: O DATA:
TLL MODE
REGISTER TO A P C REGISTER AND AD14 - RESULT IN B & C REGISTER NO-SO IF STC013* OR STC
R 23 MINOR 32 ON NO-GO
) MICROSECOND PULSE ON GTCOO1* TO POSFIX RECIEVER
TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFEOF7F EN CLK RUN TAPE STOP, E POSFIX PULSE TEST LED TIMING PULSE INTERVAL 6 ON GTCOO1*

NO.I		TEST/FAULT	I SELF-TEST PROGRAM	REMARKS
	5	F62.NGG.1	FAULT LOC WITHIN TEST T62.NGG- GTCOOl* PULSE OF INCORRECT WIDTH	*
			INDICATORS I DISPLAY I REPLACE ASSEMBLIES	ND PULSE AT ALL DN STCOOL
			11	AD POESE AT ALL DA STOOT
			INO GO I BLANK  1 A1 A2 A18        1A1 A3A (12 + 13)   	PULSE WAS PRESENT
	4	T62.NGG (CONT)	SET THE I/O COMPLETE FLAG (GTCO10*) RESET THE I/O COMPLETE FLAG (GTCO10*) BRANCH TO MAJOP 23 MINOR 34	RESET TST2
3 31			SPARE	
3 <u>3</u> 2	4	F62.NGN	"DC CLK STOP" RESET KM4091 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND GQI6000000114143413±4±7±16±231I	BKB031* ACTIVE
333			SPARE	
3 34 3 35	5	T62.NGGG	CHECK FOR FAULT IN BOTH QUT051 AND QUT052 OF MTWI READ & COMPARE MISCELLANEOUS WORD 1 WITH A00000C COMPARE THE B REGISTER TO A00000C LOGICALLY 'AND' C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS COMPARE THE B REGISTER TO A00000C BRANCH TO MAJOR 23 MINOR 37 ON ND-GD	ND-GO IF GTC001* = 0
	6	F62.NGGGG	FAULT IN RCPC SET OF GTC001* ACTIVE. OR MTWL REC EN STOP TAPE	
			I <u>INDICATORS I DISPLAY</u> NONE   BLANK  1A1A2A18   I I I I I I I I I I I I I I I I I I I	
			ll Alay Alay Alay Alay Alay Alay Alay Ala	

STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON

TESTICECISI	ION   TEST/FAULT	I SELF-TEST PROCRAM	I REMARKS
		I INDICATORS I DISPLAY I BEPLACE ASSEMBLIES I IND GO I BLANK IPROCEED PER PARAGRAPH 3=12D I	FAULT IN INST DECODE MATRIN
3 36		SPARE	
3376	F62.NGGGN	FAULT IN BIT 8 09 9 OF MTW1 REC STOP TAPE, DISPLAY C REGISTER, NO-GD LIGHT ON IINDICATORS1_DISPLAY1	
3 38		SP AR E	
3393 340	T62.NN	TEST LCU INST DECODE MATRIX, TRY INST RCFM SERIALLY LOAD THE B REGISTER WITH A READ & COMPARE THE FMB LINES WITH AFFFFFFF COMPARE THE P PEGISTER TO THE A REGISTER BRANCH TO MAJOR 23 MINOR 42 ON NO-GO	
4	F62.NNG	FAULT IN SIIC IBT OR LATCH STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GOIBLANKIIAIA2AII0+11+16}I	
3 41		SPARE	
3424	F62.NNN	FAULT IN LCU INST DECODE MATRIX STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	

TESTIDECISION		SELF-TEST PROGRAM	I REMARKS
		IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESH IND_GOI_J777777771PROCEED_PER_PARAGRAPH_3=12DH	
23 43		SP AR E	
23 44 1 23 45	T63	CHECK RESET OF "CLK CONTROL FF" USING STCL ENABLE LOW LEVEL ON GTCOOI* INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OF9FFF0FFF COMPARE THE B REGISTER TO A LOGICALLY 'AND' C REGISTER AND A00000C - RESULT IN B & C REGISTER BRANCH TO MAJOR 23 MINOR 47 ON NO-GO BRANCH TO MAJOR 23 MINOR 56	MTW1 -> IN MUX ND-go FDR gtcoo1* = 1
23 46		SPARE	
23 47 2 23 48	T63.N	ATTEMPT RESET OF "CLK CONTROL FF" WITH EOP "STOP COMP CLK" LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3E600 READ & COMPARE MISCELLANEOUS WORD 1 WITH A COMPARE THE B REGISTER TO A LOGICALLY "AND" C REGISTER AND A00000C - RESULT IN B & C REGISTER LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A00000 BRANCH TO MAJOR 23 MINOR 50 ON NO-GO	SET UP EA =0371, I/O REG INACTIVE I/O REG ACTIVE NO-GO FOR GTCOO1* = 1
3	F63.NG	F <sup>t</sup> ULT IN STCL IBT STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIESI INO GO I BLANK IIAIA2A18 II IIAIA3A13I	BAD116* SƏ1
23 49		SPARE	
23 50 3 23 51	F63.NN	ATTEMPT RESET DF"CLOCK CONTROL FF"WITH RCNU, USES"DC CLOCK STOP" ENABLE CONTROLLED TIMING PULSE INTERVAL 10 ON GTCOO1* READ & COMPARE MISCELLANEOUS WORD 1 WITH A COMPARE THE B REGISTER TO A LOGICALLY "AND" C REGISTER AND A00000C - RESULT IN B & S REGISTER BRANCH TO MAJOR 23 MINOR 53 ON NO-GO	NO-GO FOR GTCOOl* = 1

		TEST/FAULT	SELF-TEST PROGRAM	REMARKS
	4	F63.NNG	CKB123* INACTIVE STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT DN IINDICATORSI_DISPLAYI	
			IND_G0I30011A1A3A(12+131I	
23 52			SPARE	
23 53 23 54	4	T63.NNN	ATTEMPT SET OF RESET COMPUTER FLAG ENABLE COMPUTEP PESET (GTC000*) READ & COMPARE MISCELLANEOUS WORD 1 WITH A COMPARE THE B REGISTER TO A LOGICALLY 'AND' C REGISTER AND A0002 - RESULT IN B & C REGISTER BRANCH TO MAJOR 23 MINOR 55 ON ND-GO	N0~G0 FOR GTC000* = 1
	5	F63.NNNG	FAULT IN FINAL GATE OUTPUT OF GTCOD1* STOP TAPE, DISPLAY C REGISTER, ND-GD LIGHT ON	
			I <u>INDICATORS</u> I <u>DISPLAY</u> I <u>BEPLACEASSEMBLIES</u> I NO_GOI <u>BLANK</u> IIAIA3AQ2	GTC001* S@1
23 55	5	F63.NNNN	FAULT IN RESET GTCOOI* TO O STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON	
			IND_GOI2000011A1A3A16+7+12+131I	
3 56	1	<b>T</b> 64	SET UP "ANY MEM OP & CM7" TO RESET "CLK CONTROL FF" WITH "DC CLK STP", Check reset of TST2	
23 57			INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFDF0F4FFF ENABLE CONTINUOUS HIGH LEVEL ON GTC001* ENABLE SINGLE MEMORY MODE WITH ADDRESS: 0 DATA: CONTENTS OF 4 REGISTER INITIATE SELF TEST MODE 2-RETAIN PREVIOUS BIT PATTERN IN SELF TEST REG.	MTW1->INMX ON CM4121, SIV CM7, SIM ND-GO
			BRANCH TO MAJOR 23 MINOR 58 ON NO-CO SET THE I/O COMPLETE FLAG (GTCO10*) RESET THE I/O COMPLETE FLAG (GTCO10*)	RESET TST2
			TEST FOR TST2 FF NUT RESET INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFFF0F0FFF	EN MEM #1 ON CMA121, SIM CM7,
			ENABLE CONTINUOUS HIGH LEVEL ON GTCOOI* ENABLE SINGLE MEMORY MODE WITH ADDRESS: O DATA: CONTENTS OF A REGISTER	

	ON   TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
		INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF4FFF Branch to major 23 minor 63 on NO-GO Branch to major 23 minor 62	STM NO GO
3582 359	T64.1	RESET TST2 WITH LXMB PULSE THE XMB DRIVERS WITH THE A REGISTER INITIATE SELF TEST MODE 2-RETAIN PREVIOUS BIT PATTERN IN SELF TEST REG BRANCH TO MAJOR 23 MINOR 60 ON NO-GO	
3	F64.1.G	FAULT IN SLMA IBT,LATCH, OR CMA121 RESET OF TST2 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		REPLACE_ASSEMBLIES  NO GO   BLANK  1A1A2A15  IIA1A3A(1.7.15.20]	
3603	T64.1.N	ISOLATE BETWEEN FAULT IN RESET OF SELF TEST REG AND RESET OF TST2 Pulse the XMB drivers with the a register Branch to Major 23 minor 61 on NO-GO	
4	F64.1.NG	INPUT TO GYR707 S#1 Stop Tape, Display C register, NO-GO light on	
		IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES IND_GDIBLANKIZA1A3A15	1
361 4	F64.1.NN	FAULT IN"LCU B REG CLK MODE 2 ENABLE" SIDP TAPE, DISPLAY C REGISTER, NO-GO LIGHT DN	
		IINJIGATORSI_DISPLAYI	1 1 1 1
3622	F64.2	INPUT TO AYR752 SƏ1 Stop Tape, Display C register, NO-go light on	

TESTICE		I TEST/FAULT	SELF-TEST PROCRAM	I REMARKS
			I INDICATORS I DISPLAY I BEPLACE ASSEMBLIES	1
23 63 23 64	1	T65	CHECK FOR RESET OF GTC001* TO 0 SET THE I/O COMPLETE FLAG (GTC010*) RESET THE I/O COMPLETE FLAG (GTC010*) COMPARE THE B REGISTER TO A LOGICALLY 'AND' C REGISTER AND A00000C - RESULT IN B & C REGISTER BRANCH TO MAJOR 23 MINOR 66 ON NO-GO BRANCH TO MAJOR 23 MINOR 70	RESET TST2 FRDM T64 ND-GD FOR GTC001* = 1
23 65			SPARE	
23 66 23 67	2	T65.N	CHECK FOR SLMA FF NOT RESET, RESULTS IN SHT DATA EN Compare the B ?Egister to A00000C Branch to Major 23 minor 68 on ND-GO	GD IF SLMA FF IS RESET
	3	T65.NG	CHECK GTCOO1* WITH RCM1 READ & COMPARE MISCELLANEOUS WORD 1 WITH A00000C LOGICALLY "AND" C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS BRANCH TO MAJOR 23 MINOR 69 ON NO-GO	
	4	F65•NGG	FAULT IN "DC CLK STOP" RESET OF "CLK CONTROL FF" STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I INDIGATORS I DISPLAY I REPLACE ASSEMBLIES IND GO BLANK IIAIA3A14.7.131	t 1
23 68	3	F65.NN	SLMA FF NOT RESET STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIES IND_GOI2520000000CIIALA3A(1.4.7)	1
23 69	4	F65.NGN	FAULT IN TST2 LD BREG ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	

TESTICECISION			REMARKS 1
		IINDIG&TORSI_DISPLAYIBEPLACE_ASSEMBLIESI IND_GQI3QQ12A1A3A15I	
23 70 1 23 71	T66	TEST FOR NO "DC CLK STOP RESET OF GTCOO1* TO O IN CIU CLK MODE Initiate self test mode 2-load self test register with ofdfofofff	MTW1->INMX ON CM4121, SIM CM7
		ENABLE CONTINUTUS HIGH LEVEL ON GTCOOI* RESET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST CIU CLOCK MODE (GTCOO3*) ENABLE SINGLE MEMTRY MODE WITH ADDRESS: O DATA:	
		CONTENTS OF A REGISTER COMPARE THE B REGISTER TO A00000C LOGICALLY 'AND' C REGISTER AND A REGISTER-RESULT IN & & C REGISTERS BRANCH TO MAJOR 23 MINOR 72 ON NO-GO BRANCH TO MAJOR 23 MINOR 77	NO-GO IF GTCOOl* = O
23 72 2 23 73	T66.N	CHECK FOR SLMA FF NOT RESET, RESULTS IN SHT DATA EN Compare the P register to A00000C Branch to Major 23 Minor 74 on NO-GO	GO IF SLMA FF IS RESET
3	T66.NG	CHECK SIIC LATCH FOR NOT RESET READ & COMPARE MISCELLANEOUS WORD 1 WITH A01 LOGICALLY 'AND' C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS BRANCH TO MAJOR 23 MINOR 75 ON ND-GO	ND-GO IF GTC003* =1
4	F66.NGG	NO CTU CLK MODE Define NCU test tape	
		I INDICATORS I DISPLAY I BEPLACE ASSEMBLIES	RVN022 SƏ1 Ciu clk mode inactive
23 74 3	F66.NN	SLMA FF NOT RESET STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		INDICATORS I DISPLAY I BEPLACE ASSEMBLIES   INO GO  252000000001141424(19,20)  IAIA3A(1.3.7)	
23 75 4	F66.NGN	SIIC LATCH NOT RESET STOP TAPE, DISPLAY C REGISTER, ND-GD LIGHT DN	

		I TEST/FAULT		REMARKS
			IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIESI IND_GOI400000011A1A2A(10.11.16)I	
23 76			SPARE	
23 77 23 78	1	T67	TEST RESET OF "CLK CONTROL FF" WITH RCNU INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF9FFFOFFF SET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST NCJ CLOCK MODE (GTC003*) ENABLE CONTINUOUS HIGH LEVEL ON GTC001* LOAD A REGISTER WITH A999 ENABLE CONTROLLED TIMING PULSE INTERVAL 999 ON GTC001*	SET UP BIT PATTERN FOR TST FOLLOWING, MTW1->INMX
	2	F67.1	FAULT LOC WITHIN TEST T67, NOT A PROGRAMMED STOP- FAULT IN "CLK COUNTER"	
	1	T67(CONT)	IINGIGATORSI_DISPLAYIREPLACE_ASSEMBLIESI ITESI_SET_FAULT_I200000011A1A3A(6.7.8.9.10)I INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OF9FFFOFFF COMPARE THE E REGISTER TO A LOGICALLY 'AND' C REGISTER AND A00000C - RESULT IN B & C REGISTER BRANCH TO MAJOR 23 MINOR 79 ON NO-GO BRANCH TO MAJOR 23 MINOR 81	MTW1 -> IN MUX NO-GO FOR GTCOOl* = 1
23 <b>79</b>	2	Т67.2	TEST RCNC GEN PULSE ON GTC001* ENABLE LOW LEVEL ON GTC001* SERIALLY LOAD THE B REGISTER WITH A03 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH 4FBFFE077F ENABLE CONTROLLED TIMING PULSE INTERVAL 14 CONDITIONALLY ON GTC001*	SET UP CM1 DATA En LD CM, En Clk Run Tape Stop, En B->Rom, En Posfix Pulse test
	3	F67.2.1	FAULT LOC WITHIN TEST T67.2- PULSE ON GTCOO1* OF INCORRECT WIDTH IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIESI INDNEI_BLANKIIAIA3A06I IND_GOI_BLANKIIAIA3A16.7.8.9.10}I	NO PULSE PRESENT
23 80	3	F67.2.2	FAULT IN "NORMAL CLK STP",OR RCNU IBT OR LATCH SET THE I/O COMPLETE FLAG (GTCO10*) RESET THE I/O COMPLETE FLAG (GTCO10*) STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT DN	RESET TST2

TESTIDEC		TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
			IINDICATORSI_DISPLAYI	
2381 1 2382		T68	TEST SET OF COMPUTER RESET FLAG, GTCOOO* ENABLE COMPUTEP RESET (GTCOOO*) INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OF9FFF0FFF COMPARE THE B REGISTER TO A LCGICALLY 'AND' C REGISTER AND A0002 ~ RESULT IN B & C REGISTER BRANCH TO MAJOR 23 MINOR 83 ON ND-GO BRANCH TO MAJOR 23 MINOR 85	MTW1 -> [N MUX NO-go for gtcooo* = 1
23832	: 1	F68.N	FAULT IN RSET IBT OR LATCH, OR GTCO00* -> MTW1 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIESI INO GO I 2000011A1A2A(11,12,15) IIA1A4A05	
3 84			SPARE	
3 85 1 3 86	L	T69	TEST RESET OF RSET FF, GTCOOO* = 1, WITH RCNC LOAD & REGISTER WITH AFFF ENABLE CONTROLLED TIMING PULSE INTERVAL 10 CONDITIONALLY ON GTCOO1*	
2	2	F69 <b>.</b> 1	FAULT LOC WITHIN TEST T69 - LUAD CLK COUNTER BEFORE END OF DATA	I INPUT TO IKF113* OPEN
1	L	T69{CONT}	INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OF9FFF0FFF Compare the B Pecister to A0002 Logically 'AND' C register and a register-result in B & C registers Branch to Major 23 Minor 87 on NO-GO Branch to Major 23 Minor 93	MTW1 -> IN MUX NO-GO IF GTCOO1* = 0
23872 2388	2	T69•2	CHECK RCNC RESET OF GTCOO1* TO O ENABLE CONTINUAUS HIGH LEVEL ON GTCOO1* ENABLE CONTROLLED TIMING PULSE INTERVAL 10 CONDITIONALLY ON GTCOO1* READ & COMPARE MISCELLANEOUS WORD 1 WITH A LOGICALLY "AND" C REGISTER AND ADOODOC ~ RESULT IN B & C REGISTER	<b>ND-3D IF STE001* = 1 &amp; RC</b>

	I TEST/FAULT	SELF-TEST PROGRAM	REMARKS
		BRANCH TO MAJO? 23 MINOR 90 ON ND-GO INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OF9FFFOFFF Compare the B register to a Logically "And" C register and A00000C - Result in B & C register BRANCH TO MAJOR 23 MINOR 91 ON NO-GO	IBT ACTIVE MTW1 -> IN MUX NO-GO FOR GTCOO1* = 1
3	F69.2.N	FAULT IN "COMP CLK INH" RESET OF RSET FF, DR BIT OF MTW1 REC         STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON         I	
89		SPARE	
90 3	F69.2.1	FAULT IN RENE IBT OR LATCH STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINCICATOBSI_DISPLAYI	
91 3	F69.2.2	FAULT IN LCU INST DECODE MATRIX STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I INDICATORS I DISPLAY I BEPLACE ASSEMBLIES IND GOI IND GOI	
92		SP AR E	
93 l 94	т70	TEST "CONDITIONAL CLK STP" WITH RCNC UNABLE TO RESET GTC001* TO 0 SERTALLY LOAD THE B REGISTER WITH A03 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH 4F9FFF07FF ENABLE CONTINUOUS HIGH LEVEL ON GTC001* RESET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST CIU CLOCK MODE (GTC003*) ENABLE CONTROLLED TIMING PULSE INTERVAL 20 CONDITIONALLY DN GTC001* INITIATE SELF TEST MODE 1-RETAIN PREVIOUS BIT PATTERN IN SELF TEST REG.	SET UP CM1 DATA En LD CM, EN B->ROM, MTW1->INMX

TESTIDECISION			REMARKS
		BRANCH TO MAJOR 23 MINOR 95 ON NO-GO Branch to Major 23 Minor 96	
3 95 2	F70.N	CONDITIONAL CC CLK STOP LATCH NOT RESET STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		I_INDIGATORSI_DISPLAYIBEPLAGE_ASSEMBLIESI IND_GOI30011A1A3A(6,7)I	
23 96 1	771	TEST GEN DF PULSF ON GTCOO1* WITH RCNU & RCNC- PULSE MEASURED AT POSFIX RECEIVER SET INHIBIT INCPEMENT CP FLAG & ENABLE SELF TEST NCJ CLOCK MODE (GTCOO3*) INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFEOF7F	EN SLK RUN TAPE STOP, EN
		PUNCH TAPE CODES - /8 /4 #F #6 #0 #0 &C	PDSFIX PULSE TEST RCNU 005F - TEST SHORT (A) EN
2	F71.1	FAULT LOC WITHIN TEST T71- INCORRECT PULSE WIDTH I INDICATORS I DISPLAY I BEPLACE ASSEMBLIES INDRE BLANK IPROCEED PER PARAGRAPH 3-12D IND GO BLANK IPROCEED PER PARAGRAPH 3-12D ITEST SET FAULT 1 2000000 [141434(5,7)	IAR111* SƏ1
3971	<b>T71(CONT)</b>	SERIALLY LOAD THE B REGISTER WITH A03 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH 4FBFFE077F	I SET UP DATA FOR CM1 EN LD CM, EN CLK RUN TAPE STOP, EN B->ROM, EN POSF PULSE TEST
2	F71.2	ENABLE CONTROLLED TIMING PULSE INTERVAL 16 CONDITIONALLY ON GTCOO1* FAULT LOC WITHIN TEST T71- FAULT IN "CONDITIONAL CC CLK STP	
		IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIES IND_GDIBLANKIPROCEED_PER_PARAGRAPH_3=12D	1
1	<b>T71(CONT)</b>	SET THE I/O COMPLETE FLAG (GTCO10*) RESET THE I/O COMPLETE FLAG (GTCO10*)	RESET TST2
23 98 1	T72	TEST OF INPUT TO MBCO61 ENABLE VERTICAL PARITY CHECK	

ENABLE VERTICAL PARITY CHECK BRANCH TO MAJO<sup>D</sup> 25 MINOR 1

ITESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS I
I_NO_I_LEVEL_INUMBERI		

23 99 END OF MAJOR TEST

136

TESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	REMARKS
INDAI LEVEL I NUMBER I		f
		***=======*****************************

24 00	BRANCH TO MAJO? 24 MINOR 3
24 01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
24 02	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
24 03	END OF MAJOR TEST

137

ESTIDECISION   TEST/F NO_L_LEVEL_LNUMB		REMARKS
********* *	*** ***********************************	***************************************
*	EXTERNAL DATA PATHS TESTS- MAJORS 25, 26, 27, 28, 29	*
*	TESTS FOR LOGICAL FAULTS T74 - T111 Tests for shorts t112 - t121	*
* *******	***************************************	*
= 00		
5 00	INITIALIZE DEFINE SELF TEST TAPE Set invest increment of flag s enable sets test not clock node	
	SET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST NCJ CLOCK MODE (GTC003*)	
	ENABLE LOW LEVEL ON GTCOO1* Branch to major 25 minor 3	
5 01	INITIALIZE	
	DEFINE SELF TEST TAPE SET INHIBIT INFREMENT CP FLAG & ENABLE SELF TEST NCJ CLOCK MODE	
	(GTC003*)	
	ENABLE LOW LEVEL ON GTCOO1* Branch to major 25 minor 3	
5 02 2 31.2	BBC537* S21 STOP TAPE, DISPLAY C REGISTER, ND-GD LIGHT DN	
	I_INDIGATORSI_DISPLAYI	
******	*****	*****
*	TEST FOR LOGICAL FAULTS IN EXTERNAL DATA PATHS- MAJORS 25 - 28 & 29 MINDRS3 - 75	*
* *******	*******	*
5031 T74	TFST MB DR -> JEP, ROM = AFFFFFFF BUT DR NOT ENABLED => 0->QUB(001-028) PREVIOUS TEST = (23)172	
5 04	LOAD A REGISTER WITH AFFFFFF	
	COMPARE THE R REGISTER TO A	->INWX
	BRANCH TO MAJOR 25 MINOR 5 ON NO-GO Branch to major 25 minor 20	

TESTIDE		TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
25 05 25 06	2	T74.N	TEST MB DR -> KD1 REC, ROM * AFFFFFFF BUT DR NOT ENABLED => 0 -> WD1 LOAD A REGISTEP WITH AFFFFFFF INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OEBFFF0FFF COMPARE THE E REGISTER TO A BRANCH TO MAJOR 25 MINOR 11 ON NO-GO	WD1 REC->INMX
25 07	3	F74.NG	SINGLE BIT OF EB REC SP1. SET UP ERROR BIT- BIT DSPL GIVES QUBOXX S@1         LOAD A REGISTER WITH AFFFFFF         INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 088FFF0FFF         COMPARE THE B °EGISTER TO A         STOP TAPE, DISPLAY C REGISTER, ND-GD LIGHT ON         INDICATORS         INDICATORS         LOQ000000000000000000000000000000000000	JEB->IVMX
25 08 25 09 25 10			IND_GQIX01114144403 IND_GQIX0114144402 IND_GQIX114144401 SP ARE SP ARE SP ARE SP ARE	
_	3	T74.NN	TEST FOR MB DR EN SØ1 Compare the B Register to AFF8 Branch to Major 25 minor 12 on ND-Go	

4 F74.NNG FAULT IN EN OF MP DR STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON

NO.1_LEVEL	TEST/FAULT	SELF-TEST PROGRAM   	REMARK S
		IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GDIBLANKIIAIA2A04I	
5124	T74.NNN	TEST FOR MB DR EN SƏL Compare The B register to A07FC Branch to Major 25 Minor 13 on NO-GO	
5	F74.NNNC	FAULT IN EN OF MB DR STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I <u>INDICATORS</u> I <u>DISPLAY</u> IIIIAIAZAO4 IND_GOIBLANK_IIAIAZAO4	
5135	T74.NNNN	TEST FOR MB OR EN SØ1 Compare the B register to Aqqoo3FF Branch to Major 25 Minor 14 on No-Go	
6	F74.NNNNG	FAULT IN EN OF MR DR STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYI	
5146	T74.NNNNN	TEST FOR MB DR EN SƏL Compare The B register to Affffff Branch to Major 25 Minor 16 on No-30	
7	F74.NNNNNG	TOTAL MB DR EN SA1 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I INDICATORS I DISPLAY I REPLACE ASSEMBLIES IND GO I BLANK  IAIA2A(4,13,21)	
5 15		SPARE	
5167	F74.NNNNNN	SINGLE BIT OF MB DR ACTIVE. SET UP ERROR BIT- BIT DSPL GIVES DTBOXX Signal affected Compare the B pegister to a Stop tape, pisplay c register. ND-gd light on	

		TEST/FAULT	I SELF-TEST PROGRAM	 	RE MARKS
			I_INDICATORSI_DISPLAYIBEPLACE_ASSEMBLIESI		
			NO_GO1 10000000011A1A2A(4, 6)		
			ND_GD1_XX000000011A1A2A(6.7)1		
			1 NO_GO1200000011A1A2A(5,711 1 NO_GO1100000°C11A1A2A(3,5)		
			NO_GOIXXXX00I1A1A2A(3,5)		
			INO_GQ12011A1A2A13.511		
			<u>NO_GO11011A1A2A(2,3)</u> 1		
			INO_GOIXI1A1A2A12.3)I		
17			SPARE		
18			SPARE		
19			SPARE		
20 1	L -	175	TEST MB DR -> JEB, ROM=AFFFFFFF & DR ENABLED => 1->QUB(001-028)		
21			LOAD A REGISTER WITH AFFFFFF		
			INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 2BBFFFOFFF	ROM->MB,	JEB->IVMX
			COMPARE THE B REGISTER TO AFFFFFF Branch to major 25 minor 22 on NO-Go		
			BRANCH TO MAJOR 25 MINOR 22 ON NO-GO BRANCH TO MAJOR 25 MINOR 44		
			BRANCH TO HESON 25 HINDR 44		
22 2	2 .	T75.N	TEST MB DR -> WD1 REC, ROM=AFFFFFFF & DR ENABLED => 1-> WD1		
23			LOAD A REGISTED WITH AFFFFFF		
			INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 2EBFFFOFFF	ROM->MB.	WD1 REC->INMX
			COMPARE THE B REGISTER TO AFFFFFF		
			BRANCH TO MAJOR 25 MINOR 27 ON NO-GO Branch to major 25 minor 34		
24			SPARE		
25			SPARE		
26			SPARE		
27 3	3 -	175.NN	TEST FOR MB DR EN SaO		
<b>_</b>	•		COMPARE THE B REGISTER TO A007FFFF		
			BRANCH TO MAJOR 25 MINOR 28 ON ND-GO		
4	+ 1	F75.NNG	FAULT IN EN OF MP DR		

		I TEST/FAULT	SELF-TEST PROGRAM	REMARKS
			IINGIGATORSI_DISPLAYIREPLACE_ASSEMBLIESI ING_GOIBLANKIIAIA2AQ4I	
25 28	4	T75.NNN	TEST FOR MB DR EN SOO Compare the B register to Aff803Ff Branch to Majop 25 Minor 29 ON ND-GO	
	5	F75.NNNG	FAULT IN EN OF MR DR STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I <u>INDICATORS I DISPLAY</u> IND GO	
25 29	5	T75.NNNN	TEST FOR MB DR EN SQO Compare the B register to Afffc Branch to Major 25 Minor 30 on ND-Go	
	6	F75.NNNNG	FAULT IN EN OF MP DR STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I <u>INDICATORS</u> IDISPLAYI IND_GOI_BLANKIIAIA2A04I	
25 30	6	T75.NNNNN	TEST FOR MB DR EN SOO Compare the B register to a Branch to Major 25 Minor 32 on ND-GD	
	7	F75.NNNNG	TOTAL MB DR EN SPO STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I <u>INDICATORS I DISPLAY I BEPLACE ASSEMBLIES</u> IND.GOI_BLANKIIAIA2A14.19.21]	
25 31			SPARE	
25 32	۲	F75.NNNNNN	SINGLE BIT OF MB DR INACTIVE. SET UP ERROR BIT- BIT DSPL GIVES DTBOXX SIGNAL AFFECTED Compare the B register to Affffff Stop Tape, Display C register, NO-GO Light on	

ITESTIDECISION I TEST/FAULT I	SELF-TEST PROGRAM	REMARKS I
	SEEL TEST TROOMAN	KENAKS

INDICATORS	I DISPLAY I REPLACE ASSEMBLIES
NO_GO	1_1000000001141424(4.6)
i NQ_GU	1XX00000001181A2A16+71
NO_GO	i 400000011A1A2A(6+7)
NO_GO	1 200000011A1A2A15+71
NO_GO	1 10000001141424(3.5)
NO_GO	1 XXXX0011A1A2A13.5)
NO_GO	401141424(3.5)
NO_GO	1 2011A1A2A(3.5)
NO_GO	1 1011A1A2A(2.3)
NO GO	1 X[1A1A2A(2+3)

25 34	3	T75.NG	FAULT IN EB REC. REPEAT T75 TO SET UP FAULT BIT PATTERN. LODK FOR EN SOO	
25 35			LOAD A REGISTEP WITH AFFFFFF	
			INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 288FFF0FFF ROM->1	MB, JEB->INMX
			COMPARE THE B REGISTER TO A01FFFFF	
			BRANCH TO MAJOR 25 MINOR 36 DN ND-GO	

4	F75.NGG	FAULT IN EB REC EN- SOO
		STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON

I INDICATORS I DISPLAY	BEPLACE_ASSEMBLIESI
IND GO . L. BLANK	<u></u>
,	

- 25 36 4 T75.NGN TEST FOR EB REC EN SOO COMPARE THE B PEGISTER TO AFEO3FFF BRANCH TO MAJOR 25 MINOR 37 ON ND-GD
  - 5 F75.NGNG FAULT IN EB REC EN- SQO STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON

IINDICATORS_	I DISPLAY I	REPLACE_ASSEMBLIESI
1 NO_GO	1BLANK11A3	A4A20

- 25 37 5 T75.NGNN TEST FOR EB REC EN \$20 COMPARE THE B REGISTER TO AFFFC07F BRANCH TO MAJOR 25 MINOR 38 ON NO-GO
  - 6 F75.NGNNG FAULT IN EB REC EN- SOO STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON

	N   TEST/FAULT	SELF-TEST PROGRAM	REMARKS
NO.L_LEYEL	NUMBER		
		INDICATORS I DISPLAY I REPLACE ASSENBLIES	
		1 NO_GO1BLANK11A1A4A2O1	
5 38 6	T75.NGNNN	TEST FOR ER REC EN SãO	
		COMPARE THE B REGISTER TO AFFFFF8	
		BRANCH TO MAJOR 25 MINOR 39 ON NO-GO	
7	F75.NGNNNG	FAULT IN EB REC EN- SOO	
		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		INDICATORS I DISPLAY I REPLACE ASSEMBLIES	
		NO_GOIBLANKI1A1A4620I	
5 39 7	T75. NG NNNN	TEST FOR EB REC EN SOO	
		COMPARE THE B REGISTER TO A	
		BRANCH TO MAJOR 25 MINOR 41 ON ND-GO	
_			
8	F75.NGNNNN >G	TOTAL EB REC EN SOO	
		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		I <u>INDICATORS I DISPLAY I</u> <u>BEPLACE ASSEMBLIES</u>	
		``````````````````````````````````````	
5 40		SPARE	
5 41 8	F75.NGNNNN		
	>N	SINGLE BIT DF EB REC SOO. SET UP ERROR BIT- BIT DSPL GIVES QUBOXX SIGNAL	
		AFFECTED	
		COMPARE THE B REGISTER TO AFFFFFF	
		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		INDICATORS I DISPLAY L BEPLACE ASSEMBLIES	
		INO_GC1_10000000011A1A4A111	
		IND GU I_4000000011A1A4A11	
		NO_GO1_2000000011A1A4A10	

\_\_\_\_

NO_GO	1 1000000011A1A4A10	
	1400000011A1A4A10	
NO_GO	2000000114144409	1
NO_GO	11000000011A1A4A09	
	TABLE CONTINUED ON FOLLOWING PAGE	

ITESTICECIS	ION   TEST/FAULT	SELF-TEST PROGRAM	REMARSS
		TABLE_CONTINUED_EROM_PRECEEDING_PAGE	
		IND_GDI400000011a1a4a09I	
		1N0_601200000011A)A4A081	
		ND_GO1100000011A1A3A081	
		IND_GD140000011A1A4A081	
		IND_G0I20000011A1A4A07I IND_G0I10000011A1A4A07I	
		NO_G0 i4000011A1A4A07	
		INO_GOI1000011A1A4A05I	
		IND_GQIX00011A1A4A04I	
		INO 30 X0011A1A4A031	
		NO_GO1XQL1A1A4A021	
		IND_GOIX11A1A4A01I	
25 42		SPARE	
25 42		SP ARE	
23 43		J- ANE	
25 44 1	T76	TEST MB -> JEB, ROM = A0000000 & DR ENABLED #> CHECK DATA INPUTS TO MB DP For S01 Fault	
25 45		LOAD A REGISTEP WITH A0000000 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 2BBFFF0FFF COMPARE THE B REGISTER TO A BRANCH TO MAJOR 25 MINOR 46 ON NO-GO BRANCH TO MAJOR 25 MINOR 55	ROM->MB, JEB->INMX
25 46 2 25 47	T76.N	CHECK FOR FAULT IN BIT 28 Compare the B pegister to A8 Branch to Major 25 minor 48 on ND-GO	
3	F76.NG	DATA INPUT TO 28TH BIT OF MB DR S@1 STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON	
		STUP 14PE, DISPLAT C REGISTER, 10-BU LIGHT ON	
		INDICAIORS1_DISPLAY1REPLACE_ASSEMBLIES   NO_GO1BLANK11A1A2A04	
25 48 3 25 49	T76.NN	CHECK FOR FAULT IN BIT 20 - 27 OF MB DR Logically "And" C register and A7F8 - Result in B & C register Branch to Major 25 minor 51 on NO-GO	
4	F76.NNG	DATA INPUT TO BIT 1 - 19 OF MB DR S@1. STOP TAPE, CISPLAY C REGISTER, NO-GO LIGHT ON	

TESTIDECISION		I SELF-TEST PROGRAM	REMARKS
		I_INQIGATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GQLBLANKLIAIA2A03I	•
5 50		SPARE	
5514	F76.NNN	DATA INPUT TO BIT 20 - 27 OF MB DR SƏL. DSPL BIT GIVES MB DUTPUT SIGNAL- Otboxx Stop Tape, Display C register, ND-go light DN	
		1_INDICATORS1_DISPLAY1REPLACE_ASSEMBLIES	
5 52 5 53 5 54		SPARE SPARE SPARE	
5551 556	777	TEST MB DR -> ND1 REC, DR INACTIVE => O->WD1 REC INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH DEBFFFOFFF Compare the B register to A Branch to Major 25 minor 57 on ND-GO Branch to Major 25 minor 61	WD1 REC->INMX
25 57 2	F77.N	SINGLE BIT OF WD1 REC S@1. DSPL BIT GIVES SIGNAL~ 1-3 QUAOO(1-3), 4-8 QUEOO(1-5), 9-13 QUIOO(1-5), 14-28 QUP(01-15) STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON	
		INCIGATORS       I       DISPLAY       I       BEPLACE_ASSEMBLIES         IND_GD       I       100000000011A1A4A11         IND_GD       I       40000000011A1A4A11         IND_GD       I       2000000011A1A4A11         IND_GD       I       2000000011A1A4A10         IND_GD       I       2000000011A1A4A10         IND_GD       I       1000000011A1A4A10	
		IND_GDI40000000114144410 IND_GUI_20000000114144409 IND_GDI_10000000114144409 IND_GDI_10000000114144409	 
		NO_GCI200000011A1A4A08   NO_GCI100000011A1A4A08   NO_GCI40000011A1A4A08   NO_GCI20000011A1A4A07	
		IND_GC         I         10000011A1A5A07           IND_GC         I         4000011A1A5A07           IND_GC         I         200001A1A5A07           IND_GC         I         200001A1A5A07	t l

TABLE CONTINUED ON FOLLOWING PAGE

TESTID		I TEST/FAULT	SELF-TEST PROGRAM	R EM ARK S
			TABLE CONTINUED FROM PRECEEDING PAGE	
			NO GOIX00011A1A4A04I	
			IND_GOIXQI1A1A4A02I	
			IND_GOIXI1A1A4A01I	
25 58 25 59 25 60			SPARE SPARE SPARE	
5 61 5 62	1	T78	TEST MB DR -> WD1 REC, ROM = AFFFFFFF & DR ENABLED *> 1->WD1 REC LOAD A REGISTER WITH AFFFFFF INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 2EBFFF0FFF	ROM->MB, WD1 REC->INMX
			COMPARE THE B REGISTER TO AFFFFFF Branch to major 25 minor 66 on NO-GO Branch to major 25 minor 76	
25 63			SPARE	
25 64			SPARE	
5 65			SP AR E	
25 66	2	T78.N	TEST FOR WD1 REC EN SƏO Compare The 8 register to A01FFFFF Branch to Majo? 25 Minor 67 on ND-go	
	3	F78.NG	FAULT IN WD1 REC, EN SOO Stop Tape, disolay C register, NO-GO Light On	
			INDICATORS I DISPLAY I REPLACE ASSEMBLIES I BLANK ILALAGALZ	
25 67	3	178. NN	TEST FOR WD1 REC EN SØO Compare the 8 register to Afeoifff Branch to Major 25 minor 68 on ND-Go	
	4	F78.NNG	FAULT IN WD1 REC, EN SAO	

		TEST/FAULT NUMBEB	I SELF-TEST PROGRAM	REMARKS
			IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GOIBLANKIIAIA4A17I	
5 68	4	T78.NNN	TEST FOR WD1 REC EN SQO Compare the B register to Afffeoff Branch to Major 25 minor 69 on NO-GO	
	5	F78.NNNC	FAULT IN WD1 REC, EN S&O STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATOBSI_DISPLAYI	
5 69	5	T78.NNNN	TEST FOR WD1 REC EN SƏO Compare The 6 register to Affffo7 Branch to Major 25 Minor 70 on NO-go	
	6	F78.NNNNG	FAULT IN WD1 REC, EN SØO STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATOBSI_DISPLAYI	
570	6	178. NNNNN	TEST FOR WD1 REC EN S00 Compare the B register to Affffffg Branch to Major 25 Minor 71 on ND-GD	
	7	F78.NNNNNG	FAULT IN WD1 REC, EN SãO STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIESI IND_GOI_BLANKIIAIA4AI6I	
5 71	7	T78.NNNNNN	TEST FOR WD1 REC EN SOO COMPARE THE B REGISTER TO A BRANCH TO MAJOR 25 MINOR 72 ON NO-GO	
	8	F 7 8. NNNNN >G	TOTAL WD1 REC EN SOO Stop Tape, Cisplay C register, ND-go light on	

ITESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	REMARKS
I NO.I LEVEL I NUMBER	· · · · · · · · · · · · · · · · · · · ·	

	REPLACE_ASSEMBLIES
INO_GO	1424(19+21)

#### 25 72 8 F78.NNNNN

--->N

SINGLE BIT OF WD1 REC Sa1. DSPL BIT GIVES SIGNAL- 1-3 QUA00(1-3), 4-8 QUE00(1-5), 9-13 QUI00(1-5),

14-28 QUPO(01-15)

COMPARE THE B REGISTER TO AFFFFFF

STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON

INDICATORS	1 DISPLAY
	1_100000000011A1A4A11
	4000000011A1A4A11
	1_200000001141444(10.12)
	1_10000000011A1A4A10
	14000000011A1A4A101
	1 20000001141444(9,12)
	1 1000000011A1A4A09
IND_GO	1400000011A1A4A091
INO_60	1200000011A1A4A(8.121
IND_GO	1100000011A1A4A081
NO GO	140000011A1A4A081
1ND_GD	120000011A1A4A(7.121
INO_GO	110000011A1A4A07
IND_GO	
INO_GO	
INQ_GQ	<u>11000CllAlA4A05</u>
IND_GO	L400011A1A4A(4.6)
INO_GO	
ND_CO	
1 NO_GO	140011A1A4A13.6)]
IND_60	<u>20011A1A4A03</u>
INO_30	<u>10011A1A4A03</u>
INO_GO	401141444(2.6)
INO_60	.12011A1A4A02
NO_GO	11011A1A4A02
IND_GO	41141444(1+6)
IND_GD	<u>_1211A1A4A01</u>
INO_GO	111A1A4A01

25	73	SPARE
23	()	SPARE

- 25 74 SPARE
- 25 75 SPARE

 25
 76
 1
 T79
 TEST WD1\* DR -> NAD\*, ROM = AFFFFFFF BUT DR NOT EN^BLED => 1->NAD\*

 25
 77
 LOAD A REGISTER WITH AFFFFFFF

 1NITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH D7BFFF0FFF

 COMPARE THE B REGISTER TO A

 BRANCH TO MAJOR 25 MINOR 78 ON ND-GO

XMVI<-DAK

TESTICECISION	I TEST/FAULT	SELF-TEST PROGRAM	REMARKS
		BRANCH TO MAJOR 25 MINOR 98	
5782 579	179.N	TEST WD1* DR -> PJB, ROM = AFFFFFFF BUT DR NOT ENABLED => 1->PJB LOAD A REGISTER WITH AFFFFFFF	
		INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFFOFF7 Compare the B register to Affffff	PJB->RIM
		LOGICALLY "AND" C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS BRANCH TO MAJOR 25 MINOR 83 ON NO-GO	FAULT BIT PATTERN -> BREG
5803	F79.NG	SINGLE BIT OF NAD* REC ACTIVE. REPEAT 179 TO SET UP ERROR BIT- DSPL BIT GIVES BIT OF REC AT FAULT	
		LOAD A REGISTER WITH AFFFFFF INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 07BFFF0FFF Compare the B register to a	NAD->INMX
		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		INDICATORS DISPLAY BEPLACE ASSEMBLIES	
		NO_GO10000000011A1A4A19+111	
		<u>  N0_G01_10000000011A1A4A19,101101101101101101101101101101_101000000</u>	
		ND_G014000000011A1A4A101 ND_G012000000011A1A4A19+101	
		ND_GD1400000011A1A4A(9.10)1	
		NO_GOI00000011A1A4A(8.17)	
		IND_GD10000011A1A4A(7.17)I	
		NO_GO12000011A1A4A15.1711 NO_GO11000011A1A4A15.1711	
		NO_GOIX00011A184A14.17)	
		1NO_GO140011A1A4A(3,17)1	
		1 <u>N0_G01X011A1A4A(2,20)</u>   1N0_G01X11A1A4A(1,20)	i
25 81 5 82		SP AR E	
5833	T79.NN	TEST FOR WD1 DR EN SØ1 Compare the B register to AF8 Branch to Major 25 Minor 84 on NO-go	
4	F79.NNG	WD1 DR EN SØ1 Stop Tape, display C register, nd-go light on	
		150	

TESTI DE		TEST/FAULT NUBBER	I SELF-TEST PROGRAM I	REMARKS
			IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIESI INQ_GOIBLANKIIAIA2AOBI	
25 84	4 T	79.NNN	TEST FOR WDI DR EN SƏI Compare The B register to AOTC Branch to Major 25 minor 85 on ND-GD	
	5 F	79.NNNG	WD1 UR EN SƏL STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON	
			IINDICATOBSI_DISPLAYIBEPLACE_ASSEMBLIESI NO_GOIBLANKIIAIA2AOBI	
25 85	5 T	79.NNNN	TEST FOR WD1 DR EN S01 Compare the B register to A003e Branch to Major 25 minor 86 on NO-GO	
	6 F	79.NNNNG	WD1 DR EN SØ1 Stop tape, display C register, nd-go light on	
			IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GOIBLANKIIAIA2A04	
25 86	6 1	[79.NNNNN	TEST FOR WD1 DR ÉN SØ1 Compare the B register to Afffe Branch to Major 25 minor 87 on NO-go	
	7 ह	F79.NNNNNG	WD1 DR EN SƏ1 Stop Tape, display C register, ND-go light DN	
			I INDICATORS I DI SPLAY I REPLACE ASSEMBLIES I IND GO I BLANK IIAIA2A(4,13) I IIAIA3AQI	
25 87	7 1	79.NNNNNN	TEST FOR WD1 DR EN SØ1 Compare the B register to A0001F Branch to Majop 25 minor 88 on ND-GD	
		F79.NNNNNN >G	WD1 DR EN SƏ1 Stop Tape, Display C register, ND-go light on	

TESTIDECISION	I TEST/FAULT	I SELF-TEST PROGRAM I	REMARKS
		IINDIGATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GOIBLANKIIAIA2A(9.131I	
588 8	T79.NNNNN >N	TEST FOR WOL UR EN SOL Compare the B register to A00000FB Branch to Major 25 minor 89 on NO-GO	
9	F 79. NNNNN >NG	WD1 DR EN SØ1 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYI	
5899	T79.NNNNN >NN	TEST FOR WO1 DR EN SƏ1 Compare The B register to A0000007 Branch to Major 25 Minor 90 on ND-G0	
10	F 7 9. NNNNN >NNG	WD1 DR EN SØ1 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAY1REPLACE_ASSEMBLIES1 IND_GOIBLANKI1A1A2A(9,13)I	
590 10	T79.NNNNN >NNN	TEST FOR WD1 DR EN SƏ1 Compare The B register to Affffff Branch to Major 25 Minor 92 on No-go	
11	F79. NNNNNN >NNNG	WD1 DR EN SƏ1 STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON IINDICATORSI_DISPLAYI IND_GOIBLANKI]A1A2A(4:12:16:21)I	
5 91		SPARE	
59211 593	T79.NNNNN >NNNN	SINGLE BIT OF WD1* DR S@O, CHECK FOR FAULT AT BIT 14-28 Compare the B register to A	

TESTIDECIS		SELF-TEST PROGRAM	REMARKS
		LOGICALLY 'AND' C REGISTER AND AFFFE - RESULT IN B & C REGISTER BRANCH TO MAJOR 25 MINOR 94 ON NO-GO	
12	F79.NNNNNN >NNNNG	SINGLE BIT 1-13 OF WDI* DR SƏO STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		I INDICATORS I DISPLAY I REPLACE ASSEMBLIES I IND GQ I BLANK IIAIAZA09	
5 94 12	F79.NNNNN >NNNNN	SINGLE BIT 14-29 OF WD1* DR SƏO STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON	
		I INDICATORS I DISPLAY I BEPLACE ASSEMBLIES	
5 95		SPARE	
5 96 5 97		SP AR E SP AR E	
598		ENABLE VERTICAL PARITY CHECK	
599		END OF MAJOR TEST	

		TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
26 00			INITIALIZE DEFINE SELF TEST TAPE SET INHIBIT INCPEMENT CP FLAG & ENABLE SELF TEST NCU CLOCK MODE (GTC003*) ENABLE LOW LEVEL ON GTC001* BRANCH TO MAJOP 26 MINOR 3	
26 01 26 02			STOP TAPE, CISPLAY C REGISTER, NO-GO LIGHT ON STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
26 03 26 04	2	тво	TEST WD1* CR -> NAD*, RDM = AFFFFFF & DR ENABLED => 0->NAD* = 1->B REG LOAD A REGISTER WITH AFFFFFF INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 87BFFF0FFF COMPARE THE & REGISTER TO THE A REGISTER BRANCH TO MAJOR 26 MINOR 5 ON NO-GO BRANCH TO MAJOR 26 MINOR 34	RDM->WD1 DR, NAD->INMX
6 05 6 06	2	T80.N	TEST WD1* DR -> PJB, ROM = AFFFFFFF & DR ENABLED *> 0-> PJB, O->B REG LOAD A REGISTER WITH AFFFFFFF INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 8FBFFF0FF7 COMPARE THE B REGISTER TO A BRANCH TO MAJOR 26 MINOR 11 ON ND-GD BRANCH TO MAJOR 26 MINOR 24	ROM->WD1 DR, PJB->QIM
6 07 6 08 6 09 6 10			SPARE SPARE SPARE SPARE	
26 11	3	180. NN	TEST FOR WD1* DR EN SQO Compare The B register to AFB Branch to Major 26 Minor 12 On NO-Go	
	4	F80.NNG	WD1* DR EN SWO STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON (INCIGATORSI_DISPLAYIBEPLACE_ASSEMBLIES) IND_GOIBLANKIIA1A2A08	{
26 12	4	T80.NNN	TEST FOR WO1* DR EN SOO Compare the B register to A07C Branch to Major 26 Minor 13 on ND-GD	
	5	FBO.NNNG	WD1* DR EN Sao	

		TEST/FAULT	I SELF-TEST PROGRAM I	RE4ARKS 
			STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
			IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIESI IND_GDIBLANKIIAIA2A08I	
26 13	5	T80.NNNN	TEST FOR WD1* DR EN S@O COMPARE THE B ≌EGISTER TO A003E BRANCH TO MAJOR 26 MINOR 14 ON NO-GO	
	6	F80.NNNNG	WD1* DR EN SOO Stop Tape, Display C register, ND-go light DN	
			IINDICAIORSI_DISPLAYIBEPLACE_ASSEMBLIESI IND_GOIBLANKIIAIA2A04I	
26 14	6	T80. NNNNN	TEST FOR WC1* DR EN S@O Compare The B register to Afffe Branch to Major 26 Minor 15 on NO-go	
	7	FBO.NNNNG	WD1* DR EN SQO STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT DN	
			IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI	
26 15	7	T80 <b>. NN</b> NNN	TEST FOR WDI* DR EN SQO Compare the B Register to A0001F Branch to Majop 26 Minor 16 on ND-GD	
	8	T80.NNNNNN >G	WD1* DR EN SØO Stop Tape, display C register, no-go light on	
			IINDIGATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GDIBLANKIIAIA2AQ9I	
26 16	8	T80.NNNNNN >N	TEST FOR WD1* DR EN SQO Compare The B register to Accocofr Branch to Major 26 Minor 17 on NO-go	
	9	F80.NNNNNN >NG	WD1* DR EN SAO	

	LEVEL	I TEST/FAULT	SELF-TEST PROGRAM	R EM ARK S
			IINDICAIORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GOIBLANKIIA1A2A09I	
26 17	9	T80.NNNNN >NN	TEST FOR WD1* DR EN SOO Compare the B register to A0000007 Branch to Major 26 Minor 18 on NO-Go	
	10	F80.NNNNNN >NNG	WD1* DR EN SQO STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I <u>INDICATORS 1 DISPLAY 1</u> BEPLACE ASSEMBLIES IND_GOI_BLANK 11A1A2AQ9	
26 18	10	T80.NNNNNN >NNN	TEST FOR WD1* DR EN SØO Compare The B register to Affffff Branch to Major 26 Minor 20 on NO-Go	
	11	F80•NNNNNN >NNNG	WELT DR EN SOO STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIESI IND_GOIBLANKIIA1A2A14+16+211I	
26 19			SPARE	
26 20 26 21	11	T80₊NNNNNN >NNNN	SINGLE BIT OF WD1* DR SƏ1- CHECK FOR FAULT AT BIT 14-28 Compare the B register to A Logically "And" C register and AFFFE - Result in B & C register Branch to major 26 Minor 22 on ND-go	
	12	F80.NNNNN >nnnng	SINGLE BIT OF WD1* DR S@1, BIT 1~13 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT DN	

TESTID		TEST/FAULT	'  SELF-TEST PROGRAM	REMARKS
			IINDICAIOBSI_DISPLAYIBEPLACE_ASSEMBLIESI IND_GOIBLANKIIAIA2A09I	
26 22	12	F80.NNNNN >NNNNN	SINGLE BIT OF WO1* DR SQ1,BIT 14-28 Stop Tape, Display C register, ND-GD light on	
			IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GOIXXXXXXXXXIIAIA2AQ8I	
26 23			SPARE	
26 24	3	T80.NG	FAULT IN NAD* REC, REPEAT TOO TO SET UP FAULT BIT PATTERN. TEST FOR NAD* REC EN SQO	
26 25			LOAD A REGISTER WITH AFFFFFF INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 878FFF0FFF COMPARE THE B REGISTER TO A003FFFF BRANCH TO MAJOR 26 MINOR 26 DN NO-GO	ROM->WD1 DR, NAD->INMX
	4	F80.NGG	NAD* REC EN SØO Stop Tape, display C register, nd-go light on	
			IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GQIBLANKIIAIA4AI6I	
26 26	4	T80.NGN	TEST FOR NAD* REC EN SQO Compare the B register to AFFC01FF Branch to Major 26 Minor 27 on NO-Go	
	5	F80.NGNG	NAD* REC EN S?O Stop Tape, display C register, ND-GO light on	
			IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI NO_GQIBLANKIIAIA4AI6I	
26 27	5	T80. NG NN	TEST FOR NAD* REC EN SQO COMPARE THE B REGISTER TO AFFFFE BRANCH TO MAJOR 26 MINOR 28 ON NO-GO	
	6	F80.NGNNG	NAD* REC EN SÃO Stop Tape, display c register, nd-go light on	

TESTIDECIS	ION I TEST/FAULT	I SELF-TEST PROGRAM I	REMARKS
		IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GOI_BLANKLIAIA4A16I	
26 28 6	T 8 0. NG NNN	TEST FOR NAD* REC EN SQO COMPARE THE B REGISTER TO A BRANCH TO MAJOR 26 MINOR 30 ON NO-GO	
۲	F 8 0. NG NNNG	TOTAL NAD* REC SPO STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		IINDICATORSI_DISPLAYLBEPLACE_ASSEMBLIESI INO GO I BLANK IIAIA2A21 I IIAIA44A16I	
6 29		SP AR E	
26 30 7	F 80. NG NNNN	SINGLE BIT OF NAD* REC INACTIVE, SET UP ERROR BIT- DSPL BIT GIVES BIT OF REC INACTIVE Compare the R register to Affffff Enable vertical parity check STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		I INDICATORS   DISPLAY 1BEPLACE_ASSEMBLIES	
		ND_GCI40000000011A1A4A19.11)1  ND_GDJ_20000000011A1A4A19.10)  NO_GDI_10000000011A1A4A19.10]  ND_GDI_4000000011A1A4A19.	
		NO_GOI_2000000011A1A4A19.101 NO_GOI_1000000011A1A4A19.101 NO_GOI_400000011A1A4A19.101	
		INO_GOI200000011A1A4A18.171I INO_GOI100000011A1A4A18.171I INO_GOI40000011A1A4A18.171I	
		INO_GOI20000011A1A4A17.17) INO_GOI10000011A1A4A17.171 INO_GOI4000011A1A4A17.171	
		(NO_GO 120000114144415.17)	
		INO_GOIIQQQQIIAIA4A(5.17)I INO_GOIXQQQIIAIA4A(4.17)I INO_GOI4QQIIAIA4A(3.17)I	

1 2001 1A1A\$A(3,201 1 2001 1A1A\$A(3,201 1 2001 1A1A\$A(3,201 TABLE CONTINUED ON FOLLOWING PAGE

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TESTIDECISION		I SELF-TEST PROGRAM	I REMARKS
		TABLE_CONTINUED_FROM_PRECEEDING_PAGEI           IND_GOI         X011A1A4A(2.20)           IND_GOI         X11A1A4A(1.20)	
6 31 6 32 6 33		SPARE SPARE SPARE	
6341 635	T81	TEST WD1+ DR -> NAD*, RDM = A0000000 & DR ENABLED, TESTS FOR DATA INPUTS TO DR SƏ1 LOAD A REGISTER WITH A0000000 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 878FFF0FFF COMPARE THE B REGISTER TO THE A REGISTER BRANCH TO MAJOR 26 MINOR 36 ON NO-GO BRANCH TO MAJOR 26 MINOR 42	ROM->WD1 DR, NAD->INMX
6362 637	T81.N	TEST FOR INPUT TO DR S@1 AT BIT 14-28 LOGICALLY "AND" C REGISTER AND AFFFE - RESULT IN B & C REGISTER BRANCH TO MAJOR 26 MINOR 38 ON NO-GO	
3	F81.NG	DATA INPUT TO BIT 1-13 OF WD1* DR S01 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDIGATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GOIBLANKIIAIA2AQ9I	
6383	F81.NN	DATA INPUT TO BIT 14-28 OF WDI* DR SƏ1- DSPL BIT GIVES DR BIT AFFECTED STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDIGATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GOIXXXXXXXXXXXIIAIA2AOBI	
6 <b>39</b> 6 40 6 41		SPARE SPARE SPARE	
6421 643	T82	TEST WD1* DR -> PJB, DRIVER INACTIVE => 1->PJB, 1->B REG INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFFOFF7 COMPARE THE B REGISTER TO AFFFFFFF BRANCH TO MAJOR 26 MINOR 47 ON ND-GO BRANCH TO MAJOR 26 MINOR 57	PJB->RIM
6 44 6 45 6 46		SPARE SPARE SPARE	

		TEST/FAULT	I SELF-TEST PROGRAM	REMARKS
26 47	2	T82.N	TEST FOR PJB REC EN SƏO Compare The 8 register to A01FFFFF Branch to Major 26 minor 48 on NO-GO	
	3	F82.NG	PJB REC EN SOO STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
			I_INDICATORS_I_DISPLAY_IBEPLACE_ASSEMBLIESI IND_GOIBLANKIZA1A2A09I	
26 48	3	T82.NN	TEST FOR PJB REC EN SOO Compare the B register to Afeo3fff Branch to Major 26 Minor 49 On ND-Go	
	4	F82.NNG	PJB REC EN SãO Stop Tape, display c register, no-go light on	
			I INDICATORS I DISPLAY I REPLACE ASSEMBLIES I NO GO	
26 49	4	T82.NNN	TEST FOR PJB REC EN SOO COMPARE THE B REGISTER TO AFFFCO7F BRANCH TO MAJOR 26 MINOR 50 ON NO-GO	
	5	F82.NNNG	PJB REC EN SOO Stop Tape, display c register, no-so light on	
			I INDICATORS I DISPLAY I REPLACE ASSEMBLIES	
26 50	5	TB2.NNNN	TEST FOP PJB REC EN SQO Compare the P register to Affff8 Branch to Major 26 Minor 51 on NO-GO	
	6	F82.NNNNG	PJB REC EN SEO Stop Tape, display C register, NO-GD light DN	
			I_INDICAIOBSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GOIBLANKI2A1A2AQ9I	
26 51	6	T82.NNNNN	TEST FOR PJB REC EN S@O Compare The & Pegister to A Branch to Major 26 Minor 53 on NO-Go	

•		TEST/FAULT  NUMBER		
	7	F82.NNNNNG	TOTAL PJB REC EN SOO STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIESI	
			INO GO   BLANK  2A1A1A07     	
52			SPARE	
6 53	7	F82.NNNNNN	SINGLE BIT OF PJB REC SOO. SET UP ERROR BIT- DSPL BIT GIVES BIT OF REC SOO COMPARE THE B REGISTER TO AFFFFFF STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
			INDICATORS       IDISPLAY       I       BEPLACE ASSEMBLIES         IND_GD       I 10000000012A1A2A25       I         IND_GD       I X000000012A1A2A25       I         IND_GD       I X000000012A1A2A25       I         IND_GD       I X00000012A1A2A25       I         IND_GD       I X0000012A1A2A25       I         IND_GD       I XX000012A1A2A25       I         IND_GD       I XX000012A1A2A25       I         IND_GD       I XX000012A1A2A23       I         IND_GD       I XX0012A1A2A22       I         IND_GD       I XX0012A1A2A22       I	
654 655 656			S <sup>D</sup> ARE S <sup>D</sup> ARE S <sup>D</sup> ARE	
557 558	1	т83	TEST WD1* -> PJB, ROM = AFFFFFFF & DR ENABLED => 0->PJB, 0->B REG LOAD A REGISTER WITH AFFFFFFF INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH BFBFFF0FF7 ROM->WD1 DR, PJB->RIM COMPARE THE B REGISTER TO A BRANCH TO MAJOR 26 MINOR 59 ON NO-GO B4 ANCH TO MAJOR 26 MINOR 62	
6 59	2	T83•N	SINGLE BIT OF PJP REC S01 WHEN EN- DSPL BIT GIVES PIT OF REC S01         STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON         INDICATORS       I DISPLAY         IND_GO       I 100000000012A1A2A25         IND_GO       I 20000000012A1A2A25         IND_GO       I 20000000012A1A2A25         IND_GO       I 20000000012A1A2A25         IND_GO       I 2000000012A1A2A25         IND_GO       I 2000000012A1A2A25         IND_GO       I 2000000012A1A2A25         IND_GO       I 200000012A1A2A25         IND_GO       I 200000012A1A2A25         IND_GO       I 2000000012A1A2A25         IND_GO       I 2000000012A1A2A25         IND_GO       I 2000000012A1A2A25         IND_GO       I 2000000012A1A2A25         IND_GO       I 2000000012A1A2A23         IND_GO       I 2000000000000000000000000000000000000	
6 60			SP AR E SP AR E	

I_NO_L_		I TEST/FAULT	I SELF-TEST PROGRAM	REMARKS
26 62	1	T84	TFST XMB* DR -> XMB* REC, ROM = AFFFFFFF BUT DR NOT ENABLED ≠> 1->XMB*->0->B REG	
26 63			LOAD A REGISTER WITH AFFFFFF INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBDFFOFFF Compare the B register to A Branch to Major 26 Minor 64 on NO-30 Branch to Major 26 Minor 78	XMB->INMX
26 64	2	T84.N	TEST XMB★ DR -> FMB, ROM = AFFFFFFF BUT DR NOT ENABLED => 1->FMB, 1->B REG	
26 65			LOAD A REGISTER WITH AFFFFFFF INITIATE SFLF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBBFFOFFF COMPARE THE B REGISTER TO AFFFFFFF BRANCH TO MAJOR 26 MINOR 69 ON NO-GO	FMB->INMX
26 66	3	F84.NG	SINGLE BIT OF XM0* REC ACTIVE WHEN EN. REPEAT T84 TO SET UP ERROR BIT- DSPL BIT = ACTIVE REC BIT INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBDFF0FFF COMPARE THE B REGISTER TO A STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	X MB-> [ NMX
			I INDICATORS I DISPLAY L BEPLACE ASSEMBLIES	
			II	
			IIII1A1A4A12 INO GO I 400000 1A1A2A03	
			1110104012	
			INO GO I 200000/1A1A2A03	
			IND GO I 10000C 1A1A2A03	
			INO GO I XXXXX I LA LA 2A 03	
26 67 26 68			SPARE SPARE	
26 69	3	T84.NN	TEST FOR XMB* DR EN SƏL Compare The B register to A007FFFF Branch to Major 26 Minor 70 on NO~Go	

TESTIDECISION	TEST/FAULT	I SELF-TEST PROGRAM I	REMARKS
		IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI	
2670 4	T84. NNN	TEST FOR XMB* DR EN SƏ1 Compare The B register to AFF803FF Branch to Major 26 Minor 71 on ND-G0	
5	F84.NNNG	XMB* DR EN SƏL STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
26715	T84.NNNN	TEST FOR XMB* DR EN SØ1 Compare the B register to Affffc Branch to major 26 minor 72 on ND-GD	
6	F84.NNNNG	XMB* DR EN SƏL STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON I <u>INDIGATORS I DISPLAY I</u>	
26 72 6	T84.NNNNN	TEST FOR XMB* DR EN S@1 COMPARE THE B REGISTER TO A BRANCH TO MAJOR 26 MINOR 74 ON NO-GO	
7	F84.NNNNNG	TOTAL XMB* DR EN SØ1 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDIGATORSI_DISPLAYIBEPLACE_ASSEMBLIESI	
		1 <u>N0_G01BLANK11A1A2A14,13,16,211</u> I	
26 73		S <sup>o</sup> ARE	
26 74 7	T84.NNNNNN	SINGLE BIT OF XMB* DR ACTIVE, TEST FOR FAULT AT BIT 17-28 Compare the B Register to Affffff Logically "and" C register and Afff - Result in B & C register Branch to Major 26 Minor 75 on ND-GO	
8	F84.NNNNN >G	SINGLE BIT OF BIT 1-16,XM8* DR,ACTIVE	

	ECISION	TEST/FAULT	I SELF-TEST PROGRAM	t
			IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIESI INO_GOIBLANKIIAIA2A04	
26 86	4	T85.NNN	TEST FOR XMB* DR EN SOO Compare the B register to A007FC Branch to Major 26 Minor 87 on ND-GO	
	5	F85.NNNG	XMB* DR EN SOO STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I INDICATORS I DISPLAY I REPLACE ASSEMBLIES	
26 87	5	T85.NNNN	TEST FOR XMB* DR EN S@O Compare the B register to A00003FF Branch to Major 26 Minor 88 on NO-GO	
	6	F85.NNNNG	XMB* DR EN SOO STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYI	
26 88	6	T85.NNNNN	TEST FOR XMB* DR EN SQO Compare the B register to Affffff Branch to Major 26 Minor 90 on NO-Go	
	7	F85.NNNNNG	TOTAL XMB* DR EN SQO STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I <u>INDICATORS I DISPLAY</u> I <u>REPLACE ASSEMBLIES</u> IND GO	
26 89			SPARE	
26 90	7	F 8 5. NNNNN	SINGLE BIT OF XMB* DR INACTIVE. SET UP ERROR BIT- DSPL BIT ≖ INACTIVE BIT OF DR COMPARE THE B REGISTER TO A STOP TAPE, DISPLAY C REGISTER. ND-GO LIGHT ON	

TEST DECISION	I TEST/FAULT	SELF-TEST PROGRAM	REMARKS
		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT DN	
		IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIESI IND_GOIBLANKIIAIA2A01I	
6758	F84.NNNNNN >N	SINGLE BIT OF XMB* DR ACTIVE, BIT 17-28- DSPL BIT GIVES ACTIVE DR BIT STOP TAPE, DIS <sup>o</sup> lay C register, NO-GO light on	
		I_INDICATORSI_DISPLAYLREPLACE_ASSEMBLIESI IND_GOIXXXXXXXXXIIAIA2A02I	
6 76		SPARE	
6 77		SPARE	
6781	T85	TEST XMB* DR -> XMB* REC, ROM = AFFFFFFF & DR ENABLED => 0->XMB*	
6 79		REC->1->B REG LOAD A REGISTER WITH AFFFFFF INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 1FBDFF0FFF COMPARE THE B REGISTER TO AFFFFFFF BRANCH TO MAJOR 26 MINOR 80 ON ND-GD BRANCH TO MAJOR 26 MINOR 98	RJ4->XMB DR, XMB REC->INN
6802 681	T85.N	TEST XM8* DR -> FMB, ROM = AFFFFFFF & DR EN => 0->FMB->0->B REG LOAD A REGISTER WITH AFFFFFFF INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 1FBBFF0FFF COMPARE THE B REGISTER TO A BRANCH TO MAJOR 26 MINOR 85 ON ND-GD BRANCH TO MAJOR 26 MINOR 94	RDM->XM8* DR, FM8->INMX
6 82		SPARE	
683 684		SPARE SPARE	
6853	T85.NN	TEST FOR XMB* DR EN SOO Compare thê b pegister to AFF8 Branch to Major 26 Minor 86 on ND-Go	
4	F85.NNG	XM8* DR EN SQO Stop Tape, Cisplay C register, ND-go light on	

TEST DECISION   TEST/FAULT	SELF-TEST PROGRAM	REMARKS
I ND.I LEVEL I NUKBEB		

I INDICATORS	I DISPLAY I BEPLACE ASSEMBLIES
INO_GO	1 10000000011A1A2A02
	LXXX00000011A1A2A02
	140000011A1A2A02I
	<u>120000011A1A2A02</u>
	<u>110000011A1A2A01</u>
1 NO_GO	LXXXXXI1A1A2A01I

- 26 91 SPARE 26 92 SPARE
- 26 93 SPARE
- 26
   94
   3
   T85.NG
   FAULT IN XMB\* REC. REPEAT T85 TO SET UP FAULT BIT PATTERN. TEST FOR XMB\*

   26
   95
   REC EN SaO

   26
   95
   LOAD A REGISTER WITH AFFFFFFF

   INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 1FBDFF0FFF
   ROM->XMB DR, XMB REC->INMX

   COMPARE THE B REGISTER TO A
   BRANCH TO MAJOR 26 MINOR 96 ON NO-GO
  - 4 F85.NGG TOTAL XMB\* DR EN SQO STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT DN

I_INDICATORS	1 DI SPLAY	IREPLACE_ASSEMBLIESI
ING GO	I BLANK	1A1A2A21
1		<u></u>

26 96 4 T85.NGN SINGLE BIT OF XMB\* REC INACTIVE. SET UP ERROR BIT- DSPL BIT = INACTIVE BITOF XMB\* REC COMPARE THE B REGISTER TO AFFFFFFF ENABLE VERTICAL PARITY CHECK

STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON

I INDICATORS	I DISPLAY	REPLACE	ASSEMBLIES
IND GO	1000000000 1A1A		
1			;
INO GO	I XXX00000011A1A		
	1 40000011A1A		
INO GO	20000011414		
			2
INO GO	1 10000011A1A		
	TABLE CONTINUED O		
	TABLE CUNTINUED U	N FULLUWING	PAGE

 ITESTIDECISION I TEST/FAULT I
 SELF-TEST PROGRAM
 IREMARKS

 IND\_I\_LEYEL\_I\_\_NUMBEB\_\_\_\_\_
 IABLE\_CONTINUED\_ERDM\_PRECEEDING\_PAGE\_\_\_\_\_\_
 IREMARKS

 IND GO
 IXXXXX [IAIA2A03
 IIAIA4406

 IND GO
 IXXXXX [IAIA2A03
 IIAIA4406

 SPARE
 SPARE

.

26 98	ENABLE VERTICAL PARITY CHECK
	END OF MAJOR TEST

		I TEST/FAULT	I SELF-TEST PROGRAM	REMARKS
27 00			INITIALIZE DEFINE SELF TEST TAPE SET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST NCU CLOCK MODE (GTC003*) ENABLE LOW LEVFL ON GTC001* BRANCH TO MAJOR 27 MINOR 3	
27 01			STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT DN	
27 02	2	F30.3	FAULT IN 458 OF MABC Stop Tape, Display C register, ND-GO light on	
			IINDICATOBSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GOIBLANKIIAIAIA121.221I	
27 03	1	T86	TEST XMB* DR -> XMB* REC, RDM = A0000000, TEST FOR DATA INPUT TO XMB* DR	
27 04			SP1 LOAD A REGISTER WITH A0000000 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 1FBDFF0FFF COMPARE THE B REGISTER TO A BRANCH TO MAJOR 27 MINOR 5 ON NO-GO BRANCH TO MAJOR 27 MINOR 11	ROM->XMB DR. XMB REC->INMX
27 05 27 06	2	T86.N	TEST FOR FAULT AT BIT 17-28 Logically 'And' C register and Affff - Result in B & C register Branch to Major 27 Minor 7 on ND-GO	
	3	F86.NJ	DATA INPUT TO XMP* DR, BIT 1-16, S@1 SFDP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I <u>INDICATORS I DISPLAY.I</u> <u>REPLACE ASSEMBLIES</u> I IND_GOI_BLANKIAIA2AO1I	
27 07	3	F86.NN	DATA INPUT TO XMR* DR, BIT 17-28 SƏ1 STOP TAPE, [ISPLAY C REGISTER, NO-GO LIGHT DN IINDIGATORSI_DISPLAYIBEPLACE_ASSEMBLIESI IND_GOIXXXXXXXXXIIAIAZAQ2I	
27 08 27 09 27 10			SPARE S>ARE S° ልዩ E 168	
			100	

TESTICECISION	TEST/FAULT NUMBER	I         SELF-TEST PROGRAM           .1	1 REMARKS
27 12		INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBBFFOFFF Compare the B register to Affffff Branch to Major 27 Minor 16 on ND-gd Branch to Major 27 Minor 26	FMB->INMX
27 13 27 14 27 15		SPARE S⊬ARE SPARE	
27 16 2	T87.N	TEST FOR FMB REC EN SOO Compare the P register to Aolfffff Branch to Major 27 Minor 17 on NO-Go	
3	F87.NG	FMB REC EN SOO STOP TAPE, DISPLAY C REGISTER, ND-GD LIGHT DN IINDICATORSI_DISPLAYIBEPLAGE_ASSEMBLIESI IND_GDIBLANKIIAIA4A20I	
27 17 3	T87. NN	TEST FOR FMB REC EN SƏQ Compare The B register to Afeo3fff Branch to Major 27 Minor 18 on ND-Go	
4	F87.NNG	FMB REC EN SOO STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIESI IND_GOIBLANKI1A1A4A2QI	
7184	T87.NNN	TEST FOR FMB REC EN SOO Compare the R register to Afffco7f Branch to Major 27 Minor 19 on NO-Go	
5	F87.NNNG	FMB REC EN SOO STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIESI IND_GOIBLANKIIAIA4A20I	
7195	T87.NNNN	TEST FOR FMB REC EN SOO Compare the e register to Affffb Branch to majog 27 Minor 20 on NO-50	
6	F87.NNNG	FMB REC EN SOO Stop Tape, display C register, ND-GO Light DN	

TESTIDECISIC		SELF-TEST PROGRAM	REMARKS
		I INDICATORS I DI SPLAY I BEPLACE ASSEMBLIES	
27 20 6	T87.NNNNN	TEST FOR FMB REC EN SQC Compare the B pegister to A Branch to Major 27 Minor 22 on NO-GO	
7	F 8 7. NNNNNG	TOTAL FMB REC EN SÃO STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I <u>INDICATORS I DISPLAY.I</u> BEPLACE_ASSEMBLIES	
27 21		SP AR E	
27 22 7	F87.NNNNN	SINGLE BIT OF FMB REC SWO. SET UP ERROR BIT- DSPL BIT = BIT OF FMB REC SWO STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		INDICATORS       IDISPLAY       REPLACE ASSEMBLIES         IND_GD       1.100000000011A1A4A11         IND_GD       1.40000000011A1A4A11         IND_GD       1.2000000011A1A4A10         IND_GD       1.2000000011A1A4A10         IND_GD       1.2000000011A1A4A10         IND_GD       1.2000000011A1A4A10         IND_GD       1.2000000011A1A4A00         IND_GD       1.200000011A1A4A09         IND_GD       1.20000011A1A4A08         IND_GD       1.20000011A1A4A08         IND_GD       1.20000011A1A4A08         IND_GD       1.20000011A1A4A08         IND_GD       1.20000011A1A4A08         IND_GD       1.2000011A1A4A07         IND_GD       1.2000011A1A4A07         IND_GD       1.2000011A1A4A07         IND_GC       1.2000011A1A4A07	

27 23	SPARE
27 24	SPARE
27 25	SPARE

ITESTIDECISION		SELF-TEST PROGRAM	R EMARKS
27 26 1 27 27	T88	TEST XMB* CR -> FMB, ROM = AFFFFFFF & DR ENABLED => 0->FMB->0->B REG LOAD A REGISTER WITH AFFFFFF INITIATE SELF TEST MCDE 1-LOAD SELF TEST REGISTER WITH 1FBBFF0FFF COMPARE THE B REGISTER TO A BRANCH TO MAJOR 27 MINOR 28 ON NO-GO BRANCH TO MAJOR 27 MINOR 32	RDM->XMB# DR, FMB->INMX
27 28 2	F88.N	SINGLE BIT OF FMR REC S@1, DSPL BIT = BIT OF FMB REC S@1         STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT DN         INCICATORSIDISPLAY       REPLACE_ASSEMBLIES         INC GOID000000011A1A4A11         INO_GOI 4000000011A1A4A11         INO_GOI 4000000011A1A4A10         INO_GOI 200000011A1A4A10         INO_GOI 200000011A1A4A10         INO_GOI 200000011A1A4A10         INO_GOI 200000011A1A4A10         INO_GOI 200000011A1A4A00         INO_GOI 200000011A1A4A09         INO_GOI 200000011A1A4A09         INO_GOI 20000011A1A4A09         INO_GOI 20000011A1A4A09         INO_GO 100000011A1A4A09         INO_GO         INO_GO	
27 29 27 30 27 31		SP ARE SP ARE SP ARE	
27 32 1 27 33	T89	TEST XMB* DR -> JMA , DR INACTIVE => 1->JMA->1->B REG INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH ODBFFFOFFF Compare The B register to A007FFF Branch to Major 27 Minor 37 on ND-GO Branch to Major 27 Minor 45	XMVI<-AML
27 34 27 35 27 36		SP ARE SP ARE SP ARE	
27 37 2	T89.N	TEST FOR JMA REC EN SQO Compare the e pegister to addodff Branch to major 27 minor 38 on no-go	

		I TEST/FAULT	I SELF-TEST PROGRAM	1 REMARKS 1
3	3	F89.NG	J%A REC EN SƏO STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYI	
7383	3	T89. NN	TEST FOR JMA REC EN SØO Compare the B register to A007F Branch to Major 27 minor 39 on ND-GO	
4	4	F89.NNG	JMA REC EN SOO STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSL_DISPLAYIBEPLACE_ASSEMBLIESI INO_GOIBLANKIIAIA4A17I	
7 39 4	4	T89.NNN	TEST FOR JMA REC EN SOO Compare the B °EGISTER TO A Branch to Majo° 27 Minor 41 on NO-GO	
5	5	F89.NNNG	TOTAL JMA REC EN S&O STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I_INDIGATOBSIDISPLAYIREPLACE_ASSEMBLIESI IND_GOIBLANKIIA1A2A21I	
7 40			SPARE	
27 41 5	5	T89. NNNN	SINGLE BIT OF JMA REC S@O. SET UP ERROR BIT- DSPL BIT GIVES SIGNAL QUAOXX         (XX=BIT+6) AFFECTED         COMPARE THE B REGISTER TO A007FFF         STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON         I	
			IND_GOI       1000011 A1 A4 A05       I         IND_GOI       1000011 A1 A4 A05       I         IND_GOI       X0001 A1 A4 A04       I         IND_GOI       X0011 A1 A4 A03       I         IND_GOI       X0011 A1 A4 A03       I	

TABLE CONTINUED ON FOLLOWING PAGE

TESTIDECISION	TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
		TABLE_CONTINUED_FROM_PRECEEDING_PAGE           IND_GDI         4011414402           IND_GOI         2011414402	
27 42 27 43 27 44		SP ARE SP ARE SP ARE	
7 45 1 7 46	T90	TEST XMB* DR -> JMA, ROM = A007FFFO & DR ENABLED => O->JMA->O->B REG LOAD A REGISTER WITH A007FFFO INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 1DBFFFOFFF COMPARE THE R PEGISTER TO A BRANCH TO MAJOR 27 MINOR 47 ON NO-GO BRANCH TO MAJOP 27 MINOR 51	ROM->XMB* DR, JMA->IN∀X
27472	790. N	SINGLE BIT OF JMA REC S@1- DSPL BIT GIVES SIGNAL QUAOXX (XX=BIT+6)         AFFECTED         STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON         INDICATORS       1 DISPLAY         IND GD       1 100000011A1A4A08         INO GD       1 40000011A1A4A08         INO GD       1 40000011A1A4A07         IND GD       1 0000011A1A4A07         IND GD       1 0000011A1A4A05         IND GD       1 000011A1A4A05         IND GD       1 000011A1A4A05         IND GD       1 000011A1A4A05         IND GD       1 000011A1A4A05         IND GD       1 00011A1A4A05         IND GD       2011A1A4A03         IND GD       2011A1A4A02	
27 48 7 49 27 50		SPARE SPARE SPARE	
27 51 1 27 52	T91	TEST CM* DR -> JCM*, ROM = AFF80000 BUT DR NOT ENABLED => 1->JCM*->O->B REG LOAD A REGISTER WITH AFF80000 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFAFFF0FFF COMPARE THE B PEGISTER TO A BRANCH TO MAJOR 27 MINOR 53 ON NO-GO BRANCH TO MAJOR 27 MINOR 68	JCM->INMX
27 53 2	T91.N	TEST CM* DR -> WD3 REC & EXMW REC, ROM = AFF80000 BUT DR NOT ENABLED => 1->WD3&EXMW->1->B REG SIGNAL ROUTING:	

	ON   TEST/FAULT	SELF-TEST PROGRAM	REMARKS
27 54		XTM000* -> QUM046 XTM000(1*-4*) -> QUS00(1-4) XTM000(5*-8*) -> QUI00(1-4) LOAD A REGISTER WITH AFF80000 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBEFF0FFF COMPARE THE B REGISTER TO AFF001 LOGICALLY 'AND' C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS BRANCH TO MAJOP 27 MINOR 59 ON NO-GO	WD3&JEA&EXMW->INMX MASK OFF OTHER REC INPUIS
27553	F91.NG	SINGLE BIT OF JCM* REC ACTIVE. SET UP ERROR BIT BY REPEATING T91 LOAD A REGISTER WITH AFF80000 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFAFFF0FFF COMPARE THE B REGISTER TO A STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	JCM->INMX
		IINDICATORSI_DISPLAYI	IUM107 IUM106 IUM105 IUM104 IUM103 IUM102 IUM101
27 56 27 57 27 58		SP AR E S P AR E S P AR E	
27593	T91.NN	TEST FOR CM* DR EN S@1 Compare the B register to AF8 Branch to Major 27 Minor 60 on ND-GO	
4	F91.NNG	C <sup>P</sup> * DR EN SOO STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATOBSI_DISPLAYIBEPLACE_ASSEMBLIESI IND_GOBLANKIIAIA2A07	
27 60 4	T91.NNN	TEST FOR CM* DR FN S@1 Compare the B register to A0f001 Branch to Majo° 27 Minor 61 on No-go	
5	F91.NNNG	CM* DR EN SQO STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT DN	

TESTIDECI	SION   TEST/FAULT Vel 1 Number	I SELF-TEST PROGRAM	I REMARKS I
		IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GOIBLANKIIAIA2AQ7I	
27615	T91.NNNN	TEST FOR CM* DR EN SØ1 Compare the B register to Affoo1 Branch to Major 27 minor 62 on ND-GO	
6	F91.NNNNG	TOTAL CM* DR EN SƏ1 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON 1INDICATORSI_DISPLAYI	
27 62 6	T91.NNNNN	TEST FOR CM* DR EN S@1 Compare the B register to Ab0001 Branch to Major 27 Minor 64 on NO-GO	
7	F91.NNNNNG	CM* DR EN SOO STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIESI IND_GOBLANKIIAIA3AG1I	
27 63		SPARE	
27647	F91.NNNNN	SINGLE BIT OF CM* OR SQO. SET UP ERROR BIT- DSPL BIT GIVES SIGNAL SQO, XTMOXX* (XX=BIT-20) COMPARE THE B REGISTER TO A STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I	
27 65 27 66 27 67		SP AR E SP AR E	
27 68 1 27 69	T92	TEST CM* DR -> JCM*, ROM = AFF80000 & DR ENABLED => 0->JCM*->1->8 REG LOAD A REGISTEP WITH AFF80000 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 4FAFFF0FFF COMPARE THE 8 REGISTER TO AFF8 BRANCH TO MAJOR 27 MINOR 70 ON NO-GO BRANCH TO MAJOR 27 MINOR 89	ROM>CM DR. JCM->INMX

TESTIDECISION		I SELF-TEST PROGRAM	REMARKS
27 70 2	T92.N	TEST CM* DR −> ₩∿3 REC & EXMW REC, ROM = AFF800DD & DR EN => O->WD3&EXMW->O->R REG	
27 71		SIGNAL ROUTING: XTM000* -> QUM046 XTM000(1*-4*) -> QUS00(1-4) XTM000(5*-8*) -> QUI00(1-4) LOAD A REGISTER WITH AFF80000 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 4F8EFF0FFF	ROM->CM DR.
		COMPARE THE B REGISTER TO A LOSICALLY 'AND' C REGISTER AND AFFOO1 - RESULT IN B & C REGISTER BRANCH TO MAJOR 27 MINOR 76 ON NO-GO BRANCH TO MAJOR 27 MINOR 83	WD3GEXMW&JMA->INMX Mask dff other rec inputs
27 72		SPARE	
27 73 27 74 27 75		SPARE SPARE SPARE	
27763	T92.NN	TEST FOR CM* DR EN SƏO Compare The B register to AF8 Branch to Major 27 Minor 77 on No-Go	
4	F92.NNG	CM* DR EN SOO Stop Tape, display C register, ND-go light on	
		IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES	1
27774	T92.NNN	TEST FOR CM* DR EN SƏO Compare The B pegister to Aofool Branch to Major 27 Minor 78 on No-Go	
5	F92.NNNG	CM* DR EN SOO STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT DN	
		I_INDICATORSI_DISPLAYIBEPLACE_ASSEMBLIES NO_GOIBLANKIIAIA2A07	
27785	T92.NNNN	TEST FOR CM* DR EN SQO Compare the B register to Affool Branch to Major 27 Minor 80 on ND-GO	
6	F92.NNNNG	TOTAL CM* DR EN SãO STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	

TESTICECISI	ION   TEST/FAULT	I SELF-TEST PROGRAM	I REMARS
		IINCICATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_50IBLANKIIAIA2A(7+21)I	
7 79		SPARE	
7806	F92.NNNNN	SINGLE BIT OF CM* OR SƏ1. SET UP ERROR BIT- DSPL BIT GIVES SIGNAL AFFECTED, XTMOXX* (XX=BIT-20) Compare the B register to A STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		I INDICATORS I DISPLAY I BEPLACE ASSEMBLIES I NO GO	
7 81 7 82		SP AR E SP AR E	
27833 2784	T92.NG	FAULT IN JCM* REC. REPEAT T92 TO SET UP FAULT BIT PATTERN, TEST FOR JCM* EN S&O LOAD & REGISTER FITH AFF80000 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 4FAFFF0FFF COMPARE THE B PEGISTER TO A BRANCH TO MAJOR 27 MINOR 85 ON ND-GO	ROM->CM DR, JCM->INMX
4	F92.NN3	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I INDICATORSI DISPLAYI.BEPLACE ASSEMBLIES	
27854	F 92. NNN	IND_GDI 4000000011A1A4A11.11) IND_GOI 2000000011A1A4A11.10 IND_GDI 10000000011A1A4A12.101 IND_GDI 4000000011A1A4A12.101 IND_GDI 4000000011A1A4A12.101	I UM1 06 I UM1 05 I UM1 04

I SELF-TEST PROGRAM	REMARKS
IABLE_CONJINUED_EROM_PRECEEDING_PAGE         INO_GOI       400000011A1A4A14x91         INO_GOI       200000011A1A4A14x81	EUM101 TUM100
SPARE SPARE SPARE	
TEST DATA INPUT TO CM* DR FOR SƏ1. CM* DR -> JCM*, ROM = A0000000 & DR EN LOAD A REGISTER WITH A0000000 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 4FAFFF0FFF COMPARE THE B REGISTER TO A BRANCH TO MAJOR 27 MINOR 92 ON ND-GO BRANCH TO MAJOR 27 MINOR 98	I RO4->CM+ DR, JC4+->INMX
S° ARE	
DATA INPUT TO CM+ DR S@1- DSPL BIT GIVES SIGNAL AFFECTED XTMOXX {XX=BIT-20} STOP TAPE, DISPLAY C REGISTER, ND-GD LIGHT ON	
IINDICATORS1_DISPLAY1REPLACE_ASSEMBLIES1 NO_GO1BLANK11A1A2A07	1
SP ARE SP ARE SP ARE SP ARE	
	TABLE CONJINUED_EROM_PRECEEDING_PAGE         IND_GO

27 98ENABLE VERTICAL PARITY CHECK27 99END OF MAJOR TEST

		TEST/FAULT 1NUMBER	I SELF-TEST PROGRAM	REMARKS
28 00			INITIALIZE DEFINE SELF TEST TAPE SET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST NCU CLOCK MODE (GTC003*) ENABLE LOW LEVEL ON GTC001* BRANCH TO MAJO° 28 MINOR 3	
8 01			STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT DN	
28 02 28 03	1	Т94	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON TEST CM* DR & OTO DR -> WD3 REC & EXMW REC, DR INACTIVE => 1->B REG	
			SIGNAL ROUTING: XTM000* -> QUM046 XTM000(1*-4*) -> QUS00(1-4) XTM000(5*-8*) -> QUI00(1-4) XTD101 -> QUM041 XTD102 -> QUM045 XTD103 -> QUM044 XTD104* -> QUM047	
8 04			INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBEFFOFFF Compare the B register to Affoo3 Logically 'And' C register and Affoo3c8 - Result in B & C register Branch to Major 28 Minor 5 on NO-go Branch to Major 28 Minor 25	WD3&JEA&EXMW->INMX Mask off other rec inputs
8 05	2	T94.N	TEST QTD(101-103) DR -> DOWD, DR INACTIVE	
			SIGNAL ROUTING: XTD101 -> QUD007* XTD102 -> QUD011* XTD103 -> QUD010*	
8 06			INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFF0FDF COMPARE THE 8 REGISTER TO A32 LOGICALLY "AND" C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS BRANCH TO MAJOR 28 MINOR 12 ON NO-GO	COWD & MDPL -> RIM Mask off other rec inputs
28 07	3	T94.NG	TEST QTD104* DR -> MTW2 REC, DR INACTIVE	
			SIGNAL ROUTING: XTD104* -> QUT021 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFF0FEF COMPARE THE 6 PEGISTER TO A00008 LOGICALLY 'AND' C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS BRANCH TO MAJOR 28 MINOR 14 ON NO-GO BRANCH TO MAJOR 28 MINOR 16	MTW2->RIM Mask off other rec inputs

		I TEST/FAULT	I SELF-TEST PROGRAM	1 REMARKS
28 08 28 09 28 10 28 11			SPARE - SPARE - SPARE SPARE	
28 12	3	F94.NN	SINGLE BIT OF OTO DR SƏ1 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYI	XTD102 XTD103
28 13			SP AR E	
28 14	4	F94.NGN	OTDIO4* DR SOO STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIESI IND_GOI400011A1A4A119.20}	XTD104 <b>*</b>
28 15			SPARE	
28 16 28 17	4	T94.NGG	FAULT IN WD3 REC OR EXMW REC. REPEAT T94 TO SET UP FAULT BIT PATTERN, TESTFOR WD3 REC FN S@O INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBEFFOFFF COMPARE THE B REGISTER TO AFF003 LOGICALLY 'AND' C REGISTER AND AFF003C8 - RESULT IN 8 & C REGISTER COMPARE THE B PEGISTER TO AF BRANCH TO MAJOR 28 MINOR 18 ON NO-GO	HD3&JEA&EXMW->INMX Mask off other rec inputs
	5	F94.NGGG	WD3 REC EN SQO STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYIBERLACE_ASSEMBLIESI IND_GOBLANKIAIA4A19I	
26 18	5	T94.NGSN	TEST FOR WD3 REC EN SDO Compare the B pegister to Aof Branch to Major 28 Minor 19 on ND-Go	
	6	F94.NGGNG	WD3 REC EN SAC STOP TAPE, DISPLAY C REGISTER, NO-SO LIGHT ON	

		I TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
			IINCICATORSI_DISPLAYIREPLACE_ASSEMBLIES	
28 19	6	T94.NGGNN	TEST FOR WD3 REC EN SQO Compare the B register to AFF Branch to Major 28 Minor 20 on NO-Go	
	7	F94.NGGNNG	WD3 REC EN SØO STOP TAPE, CISPLAY C REGISTER, NO-GO LIGHT ON IINDIGAIOBSI DISPLAYIREPLACE_ASSEMBLIESI IND_GDIBLANKIIAIA4A19	
28 20	7	T94.NGGNNN	TEST FOR EXMW REC EN SOO Compare the B register to A00003 Branch to Major 28 Minor 22 on ND-GD	
	8	F94.NGGNNN >G	TOTAL EXMW REC EN SOO STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON IINDICATOBSI_DISPLAYIBEPLACE_ASSEMBLIES IND_GDIBLANKIIA1A4420	!
28 21			SPARE	
28 22	8	F94.NGGNNN >N	SINGLE BIT FAULT IN WD3 REC OR EXMW REC. SET UP ERROR BIT COMPARE THE B PEGISTER TO A STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON	
			IINDICAIOBSI_DISPLAY_I	QUI014 QUI013 QUI012 QUI011 QUS004 QUS003 QUS002 QUS001 QUS001 QUM047

TESTIDECISION	TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
		TABLE CONTINUED FROM_PRECEDING_PAGE	
		IND_GDI40011A1A4A03	QUM046
			QUM045
			QUM044
			QUM041
		IND_GOI1011A1A4A02	200071
8 23		SPARE	
8 24		SPARE	
8251	T95	CM+ DR & QTD DR -> WD3 REC & EXMW REC, DR ACTIVE	
		SIGNAL ROUTING:	
		XTMOOD* -> QUMO46	
		XTM000(1+-4+) -> QUS00(1-4)	
		XTM000(5*-8*) -> QUIO0(1-4)	
		XT0101 -> QUM041	
		XTD102 -> QUM045	
		XTD103 -> QUM044	
		XTD104# -> QUM047	
8 26		LOAD A REGISTER WITH AFF8	
0 20		INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 4FBEFFOFFF	ROM->CM DR, WD3&EXMW&JEA->INMX
		COMPARE THE B REGISTER TO ADDOODC8	
		LOGICALLY "AND" C REGISTER AND AFFO03C8 - RESULT IN B & C REGISTER BRANCH TO MAJOR 28 MINOR 27 ON NO-GO BRANCH TO MAJOR 28 MINOR 37	MASK OFF OTHER REC INPUT
8272	795.N	QTD(101-103) CR -> DOWC REC, DR ACTIVE	
		SIGNAL ROUTING:	
		XTD101 -> QUD007*	
		XTD102 -> QUD011*	
		XTD102 -> QUD010*	
8 28		INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 4F8FFF0FDF	EN QTD, DOWD->RIM
0 20		COMPARE THE 8 REGISTER TO A	
		LOGICALLY 'AND' C REGISTER AND A32 ~ RESULT IN B & C REGISTER	MASK OFF OTHER REC INPUT
		BRANCH TO MAJOR 28 MINOR 31 ON NO-GO	MASK OFF DIREK KEU INFOI
8293	T95.NG	TEST QTD104* DR -> MTW2 REC, DR ACTIVE	
		SIGNAL ROUTING:	
		XTD104* -> QUT021	
		INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 4FBFFF0FEF	EN QTD, MTW2->RIM
		COMPARE THE B REGISTER TO A	
		LOGICALLY 'AND' C REGISTER AND A00008 - RESULT IN B & C REGISTER Branch to major 28 minor 33 on ND-GO	MASK OFF OTHER REC INPUT
8304	F95.NGG	SINGLE BIT OF WD3 REC OR EXMW REC AT FAULT. REPEAT T95 TO SET UP E3RD3	

_NO_1LEYEL1		ENABLE VERTICAL PARITY CHECK SERIALLY LOAD THE B REGISTER WITH AFF8 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 4FBEFF0FFF COMPARE THE B REGISTER TO A00000C8 LOGICALLY "AND" C REGISTER AND AFF003C8 - RESULT IN B & C REGISTER STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	ROM->CM DR↓ ₩D3&EXMW&JEA->INMX MASK OFF OTHER REC INPUTS
		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		IINDICATORS       IDISPLAY       IREPLACE_ASSEMBLIES         IND_GD       ID0000000011A1A4A11       I         IND_GD       I40000000011A1A4A10       I         IND_GD       I20000000011A1A4A10       I         IND_GD       I20000000011A1A4A10       I         IND_GD       I2000000011A1A4A10       I         IND_GD       I2000000011A1A4A10       I         IND_GD       I2000000011A1A4A10       I         IND_GD       I2000000011A1A4A10       I         IND_GD       I2000000011A1A4A00       I         IND_GD       I2000000011A1A4A09       I         IND_GD       I000000011A1A4A09       I         IND_GD       I000000011A1A4A09       I         IND_GD       I00011A1A4A09       I         IND_GD       I00011A1A4A09       I         IND_GD       I00011A1A4A03       I         IND_GD       I00011A1A4A03       I         IND_GD       I0011A1A4A03       I         IND_GD       I0011A1A4A03       I         IND_GD       I0011A1A4A03       I         IND_GD       I0011A1A4A03       I	QUI013 QUI012 QUI011 QUS004 QUS003 QUS002 QUS001 QUM047 QUM045 QUM045 QUM044
:8313 F95	5.NN SI	INGLE QTD DR S@0 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYI	XTD103
8 32	SF	P AR E	
28 33 4 F9	5.NGN Q1	TD104* DR SƏI ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GOI	
28 34 28 35 28 36	SF	PARE PARE PARE	
28 37 1 794	6 TI	EST QTD DR -> DOWD REC, DR INACTIVE	

TESTIDE		I TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
28 38			XTD101 -> QUD007* XTD102 -> QUD001* XTD103 -> QUD010* INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFF0FDF COMPARE THE B REGISTER TO A32 LOGICALLY 'AND' C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS BRANCH TO MAJOR 28 MINOR 39 ON ND-GO BRANCH TO MAJOR 28 MINOR 45	DOWD & MDPL -> RIM MASK OFF OTHER REC INPUTS
28 39 28 40	2	T96.N	TEST FOR DOWD REC EN SOO COMPARE THE B PEGISTER TO A32 LOGICALLY MANDM C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS BRANCH TO MAJOR 28 MINOR 41 ON NO-GO	MASK OFF OTHER REC INPUTS
28 41	3	F96.NN	SINGLE BIT OF DOWD INACTIVE. SET UP ERROR BIT Enable vertical parity check Compare the B register to A Stop Tape, display c register, no-go light on	
			IINDICATORSL_DISPLAYBEPLACE_ASSEMBLIESI	QUD011*
			112A1A3A30 (NO GO   1000000012A1A2A(19,25)	QUD010*
			2A1A3A29  ND_GO 1000000012A1A2A(19,24) 	OUD007*
28 42 28 43 28 44			SPARE SPARE SPARE	
8 45	1	<b>1</b> 97	TEST OTD DR -> DOWD REC, DR ACTIVE	
8 46			SIGNAL ROUTING: XTD101 -> QUD007* XTD102 -> QUD011* XTD103 -> QUD010* INITIATE SELF TEST MODE 1-LDAD SELF TEST REGISTER WITH 4FBFFF0FDF COMPARE THE R REGISTER TO A LOGICALLY "AND" C REGISTER AND A32 - RESULT IN 8 & C REGISTER BRANCH TO MAJOR 28 MINOR 47 ON NO-GO BRANCH TO MAJOR 28 MINOR 51	EN QTD, DOWD->RIM Mask off other reg inputs
28 47	2	F97.N	SINGLE BIT OF DOVD REC ACTIVE Enable vertical parity check Stop Tape, display c register, no-go light on	

	, #+ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~	
TEST DECISION   TEST / FAULT	SELF-TEST PROGRAM	REMARKS
I_NO.L_LEVEL_LNUKBEBL		

	I_INDICATOBSI_DISPLAYIBEPLACE_ASSEMBLIES	
	NO GO   2000000012A1A2A(19,25)	QUD011*
	<u> 241A3A30</u>  NO_GO100000000 241A2A(19,25)	
		1 200010+
	NO GO   10000000 2A1A2A(19,24)	
	'	'
28 48	SPARE	
28 49	SP AR E	
28 50	SPARE	
<b>28 51 1 1</b> 98	TEST QTD DR -> MTW2 REC, DR ACTIVE	
	SIGNAL ROUTING:	
	XTD104* -> QUT021	
28 52	INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 4FBFFF0FEF	EN QTD, 4TW2->RIM
	COMPARE THE B PEGISTER TO A	
	LOGICALLY 'AND' C REGISTER AND A00008 - RESULT IN B & C REGISTER Branch to major 28 minor 53 on NO-Go Branch to major 28 minor 57	MASK OFF OTHER REC INPUTS
28 53 2 F98.N	MTW2 BIT 12 ACTIVE Enable vertical parity check Stop Tape, display c register, no-30 light on	
	INDICATORS I DISPLAY I BEPLACE ASSEMBLIES	
	1ND_G3400012A1A2A22	QUT021 SƏ1
28 54	SP AR E	
28 55	S⊐ ARE	
28 56	SPARE	
28 57 1 T99	TEST DIHR* DR & CFLG* DR & QTD*DR ~> MTW2 REC, DR INACTIVE => 1->MTW2->1->B REG	
28 58	SIGNAL ROUTING: XTD(001-018)* -> QUT(037-022)&QUC030 GTC012* -> QUP000 XTD104* -> QUT021 LOAD A REGISTER WITH AFFF7800 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFF0FEF COMPARE THE B PEGISTER TO AFFFFE BRANCH TO MAJOR 28 MINOR 59 ON NO-GO BRANCH TO MAJOR 28 MINOR 85	MTW2->RIM

	LEVEL	I TEST/FAULT	SELF-TEST PROGRAM	REMARKS
28 59 28 60	2	199.N	TEST DIHR* DR -> DOWD REC, OR INACTIVE LOAD A REGISTER WITH A0000000	
			INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFFOFDF COMPARE THE B REGISTER TO A0018	DOWD & MDPL -> RIM
			LOGICALLY '4ND' C REGISTER AND A0138 - RESULT IN B & C REGISTER Branch to major 28 minor 67 on ND-Go	MASK OFF OTHER REC INPUTS
			TEST DIHR* DR -> JEA*, DR INACTIVE	
			STGNAL ROUTING:	
			INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBEFFOFFF Compare the B register to a	JEA->RIM
			LOGICALLY "AND" C REGISTER AND ADOFFC - RESULT IN B & C REGISTER BRANCH TO MAJOR 28 MINOR 67 ON NO-GO	MASK OFF OTHER REC
28 61			SPARE	
28 62	4	<b>T99.NG</b> G	TEST CFLG* DR -> MTW1 REC, DR INACTIVE	
			SIGNAL ROUTING:	
			* GTC012* -> QUT011 INITIATE SELF TEST MGDE 1-LOAD SELF TEST REGISTER WITH GF9FFF0FFF	MTW1->INMX
			COMPARE THE B PEGISTER TO A002 Logically 'And' C register and a register-result in B & C registers Branch to Major 28 Minor 76 on ND-go	MASK OFF OTHER REC INPUTS
28 63	5	T99.NGGG	TEST FOR EN TO, DIHR SINGLE BIT OR PAIR, SOL	
			LOAD A REGISTER WITH AFFF7800 Initiate self test mode 1-load self test register with ofbfffofdf	DOWD & MDPL -> RIM
			COMPARE THE B REGISTER TO A0018 Logically 'And' C register and A0178 - result in B & C register Branch to Majop 28 minor 79 on ND-go	MASK OFF OTHER REC INPUTS
			LOAD A REGISTER WITH AFFF78 Initiate self test mode 1-load self test register with ofbeffofff	JEA->RIM
			COMPARE THE B REGISTER TO A Logically "And" C register and adoffc - result in B & C register	MASK DEE DIHER REC
			BRANCH TO MAJOR 28 MINOR 79 ON NO-SO	
28 64	6	F99.NGGGG	FAULT IN MTW2 REC. REPEAT T99 TO SET UP FAULT BIT PATTERN ENABLE VERTICAL PARITY CHECK	
			LDAD A REGISTER WITH A0000000	4710 S. S. S. M.
			INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFFOFEF COMPARE THE B REGISTER TO AFFFFE	MTW2->RTM
			STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	

TESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	REMARKS 1
NO.L LEVEL 1 NUMBER 1		

INDICATORS	I DISPLAY IREPLACE ASSEMBLIES	1
NO GO	1777776000 2A1A1A07	AAEOSIA SOO OR AAEOSIB S
	<u>12A1A2A09</u> _	1 OR FYR551# SƏ1
NO_GO	10000000012A1A2A25	QUT037
NO_GO	1_4000000012A1A2A25	I QUT036
INO_GO	1_2000000012A1A2A25	QUT035
NO_GO	1 1000000012A1A2A#5	I QUT034
NO_GO	1400000012A1A2A24	QUT033
NO_GO	_1200000012A1A2A24	I QUT032
NO_GO	_1100000012A1A2A24	I QUT031
NO_GO	<u>1400000012A1A2A24</u>	QUT030
NO_GO	20000012A1A2A24	QUT029
NO_GO	_I100000012A1A2A24	I QUT028
NO_GO	<u> </u>	QUT027
NO_GO	_I20000012A1A2A23	I QUT026
NO_GO	1 10000012A1A2A23	QUT025
NO_GO	14000012A1A2A23	] QUT024
ND_GO	12000012A1A2A23	I QUT023
NO_GO	1000012A182A23	QUT022
NO_GO	1400012A1A2A22	QUT021
NO_GO	1 200012A1A2A22	
NO_GO	1 1000/2A1A2A22	I QUB000

#### 28 65 SPARE 28 66 SPARE

28 67	3	T99. NN	SINGLE BIT OF DIHR* DR S@O. REPEAT T99 FOR FAULT PATTERN,CHECK SCU	
			SECTIONOF DIHR	
28 68			LOAD A REGISTER WITH A0000000	
			INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFFOFEF	MTW2->RIM
			COMPARE THE B REGISTER TO AFFFFE	
			LOGICALLY "AND" C REGISTER AND AOOD7 - RESULT IN B & C REGISTER	
			BRANCH TO MAJOR 28 MINOR 69 ON NO-GO	
			BRANCH TO MAJOR 28 MINOR 71	

28 69 4 F99.NNN SINGLE BIT OF DIHR\* DR, SCU SECTION, SAO ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON

I.INDICATORS	I DISPLAY 1	REPLACE ASSEMBLIES
	XXXXXXXXXXXXXX	

- 28 70 SPARE
- 28
   71
   4
   T99-NNG
   SINGLE BIT OF LCU SECTION OF DIMR\* DR S@O, CHECK BITS 25-28

   28
   72
   LOAD A REGISTER WITH A0000000
   INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFF0FEF

	ECISION	J TEST/FAULT	I SELF-TEST PROGRAM	REMARKS
			COMPARE THE B REGISTER TO AFFFFE Logically "And" c register and af - result in b & c register Branch to major 28 minor 73 on NO-GO	
	5	F99. NNGG	SINGLE BIT OF DIHR* OR XTD(006-009,011,018)* S@O ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
			I <u>INDICATORS I DISPLAY I REPLACE ASSEMBLIES</u> IND GOI_BLANKIIAIA2A(II8.23) BRANCH TO MAJOR 28 MINOR 93 ON NO-GO	- - 1 - 1
8 73	5	F99. NNGN	SINGLE BIT OF DIHR* DR XTD(001-004)* S20 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
			I INDICATORS I DISPLAY I BEPLACE ASSEMBLIES	- - -1
8 74 8 75			SPARE SPARE	
B 76	5	F99.NGGN	CFLG* DR GTCO12* ACTIVE ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON /	
877 878			SPARE SPARE	
879 880	6	T99.NGGGN	ISOLATE FAULT IN EN DIHR BETWEEN LCU & SCU LOAD A REGISTER WITH AFFFFFF INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFF0FEF COMPARE THE B REGISTER TO AFFFFE LOGICALLY 'AND' C REGISTER AND A00D7 - RESULT IN B & C REGISTER BRANCH TO MAJOR 28 MINOR 81 ON ND-GO	MTW2->RIM
	7	F99.NGGGNG	FAULT IN EN DIHR, LCU SECTION, SINGLE OR PAIR EN ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	

TESTIDECTS	SION   TEST/FAULT (EL  NUMBER	I SELF-TEST PROGRAM	I REMARKS
		IINDICATORSI_DISPLAY_IREPLACE_ASSEMBLIESI IND_GOI_BLANKIIAIA2A23I	
28 81 7	F99.NGGGNN	FAULT IN EN DIHR, SCU SECTION, SINGLE OR PAIR EN Enable vertical parity check stop tape, display C register, ND-GO light on	
•		I INDICATORS I DISPLAY I BEPLACE ASSEMBLIES	
28 82 28 83 28 84		SPARE SPARE SPARE	
28 85 1 28 86	<b>T</b> 100	TEST DIHR* DR -> MTW2 REC, DR ACTIVE Load discrete input word (Eip/Eop code) with AFFF78	
2	F100.1	FAULT LOC WITHIN TEST TIOD, NOT A PROGRAMMED STOP- CAN NOT RESET KRDO31	
		I INDICATORS I DISPLAY I BEPLACE ASSEMBLIES	1
		INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFF0FEF Compare the B register to A Logically 'And' C register and Affff4 - Result in B & C register Branch to Major 28 Minor 87 on NO-GO Branch to Major 28 Minor 98	MTW2->RIM
28 87^22 28 88	T1 00. 2	TEST DIHR* DR -> DOWD REC, DR ACTIVE LOAD DISCRETE .NPUT WORD (EIP/EOP CODE) WITH AFFF78 INITIATE SELF TEST MODE I-LOAD SELF TEST REGISTER WITH OFBFFF0FDF COMPARE THE B REGISTER TO A016 LOGICALLY 'AND' C REGISTER AND A0138 - RESULT IN B & C REGISTER BRANCH TO MAJOR 28 MINUR 89 ON NO-GO	DOWD & MDPL -> RIM Mask off other rec inputs
		TEST DIHR* DR -> JEA*, DR ACTIVE INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBEFFOFFF COMPARE THE B REGISTER TO ADOFFC	JEA->RIM
		LOGICALLY 'AND' C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS BRANCH TO MAJOR 28 MINOR 89 ON NO-GO	MASK OFF OTHER REC
3	F100.2.G	SINGLE BIT OF MTW2 REC S@1. REPEAT TIOO TO SET UP ERROR BIT Enable vertical parity check Initiate self test mode 1-load self test register with ofbfffofef Compare the B register to A	MTW2->RIM

TESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
INO, LEVEL I NUMBER L		

#### STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON

I_INDICATORS	1 DI SPLAY 1 REPLACE ASSEMBLIES	1
IND GO	1 100000000124142425	I QUT03
NO GO	1 4000000012A1A2A25	I QUTO3
INO_GO	1 2000000012A1A2A25	I QUT03
1 NO_GO	1_1000000012A1A2A25	I QUTO3
NO GO	1 400000012A1A2A24	I QUTO3
NO_GO	12000000012A1A2A24	I QUT03
IND GO	1 100000012A1A2A24	I QUTO3
NO_GO	1 400000012A1A2A24	I QUT03
NO_GO	1 200000012A1A2A24	I QUTO2
NO GO	1 100000012A1A2A24	I QUT02
NOO	40000012A1A2A23	I QUTO2
IND_GO	120000012A1A2A23	I QUTO2
IND_GO	1 10000012A1A2A23	I QUTO2
NO GO	1 4000012A1A2A23	1 QUT02
NO_GO	12000012A1A2A23	I QUTO2
INO_GO	1000012A1A2A23	I QUT02
NO_GO	400012A1A2A22	I QUTO2
NO_GO	1200012A1A2A22	QUC03
NO GO	1 100012A1A2A22	1 QUB00

\_\_\_\_\_

28 89	3	T100.2.N	TEST FOR DIHR EN SOO. REPEAT T100 TO SET UP FAULT BIT PATTERN
28 90			INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFFOFEF
			COMPARE THE B REGISTER TO AFF284
			LOGICALLY 'AND' C REGISTER AND AFFFF4 - RESULT IN B & C REGISTER
			BRANCH TO MAJOR 28 MINOR 91 ON ND-GO

MTW2->RIM

1

4 T100.2.NG EN OF LCU SECTION OF DIHR S@O ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON

I_INDICATORS	I DI SPL	YI	REPLACE	SSEMBLIES
ING GO		K  1A1A		
1		L2A1A	2 4 2 6	

- 28 91 4 T100.2.NN TEST FOR ALL BITS OF DIHR\* DR INACTIVE COMPARE THE B REGISTER TO AFFFE BRANCH TO MAJOR 28 MINOR 95 ON NO-GO
- 28 92 5 T100.2.NNG TEST FOR LDSI -> CLEAR A REG SERIALLY LOAD THE B REGISTER WITH FFFF7800 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH AFFF78 COMPARE THE B REGISTER TO THE A REGISTER BRANCH TO MAJOR 28 MINOR 93 ON NO-GO

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F100.2.NNG
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6

--->G TOTAL EN OF DIHR SOO

NO.1_LEVEL	TEST/FAULT <u>LNUMBER</u>	SELF-TEST PROGRAM	REMARKS
		ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATOBSIDISPLAYREPLACE_ASSEMBLIESI IND_GOIBLANKI2A1A2A26I	
8936	F100.2.NNG >N	FAULT IN LDSI IBT OR FF OR INPUT TO"CL A REG *1" ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON	
		INDICATORS I DISPLAY I REPLACE ASSEMBLIES I NO GO   37712A1A1A(1,2)   2A1A2A(7,13)   0R   0R   0R   0R   0R   0R   0R   0R	
894		SPARE	
8955	T100.2.NNN	SINGLE BIT OF DIHR* DR SƏ1, ISOLATE BETWEEN LCU & SCU Compare the B register to A Logically 'And' C register and AFF284 - result in B & C register Branch to Major 28 Minor 96 on NO-Go	
6	F100.2.NNN >G	SINGLE BIT OF SCU SECTION OF DIHR* DR SƏ1 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		I INDICATORS I DISPLAY I REPLACE ASSEMBLIES	
8966	T100.2.NNN >N	CHECK XTD(001-004)* FOR SƏ1 Logically 'And' C register and AF - result in B & C register Branch to Major 28 Minor 97 on No-go	
7	F100.2.NNN >NG	SINGLE BIT OF DIHR* DR S&1, XTD(005-009,011,018)* ENABLE VERTICAL PARITY CHECK	

	I REMARKS	
	KEMANNO	
		SELF-TEST PROGRAM
		TERTARCETSTON   TEST/FAIDT
No - 11		TESTIDECISION I TEST/FAULT I SLEFTEST ROOMAN

	DEDLACE ASSEMBLIES
I INDICATORS 1 DI	PLAYREPLACE_ASSEMBLIES
	LANK 11A1A2A(18,23)
INU_UU	

28 97 7 F100.2.NNN --->NN SINGLE BIT OF XTO(001-004)\* S@1 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER.

IABI	LE VER TAPE,	DISPLAY	C REGI	STER.	NO-GO	LIGHT	ON	
	1	NDICATOR	s1_0	DISPLAY	<u>(                                    </u>		REPLACE	SSEMBLIES

I_INDICATORS I_DISPLAY IREPLACE_ASSEMBLIES	- !
ING_G0	_ (

28 98 ENABLE VERTICAL PARITY CHECK

28 99 END OF MAJOR TEST

192

	LEVEL	N   TEST/FAULT	I SELF-TEST PROGRAM	REMARKS
29 00	2	F30.4 F154.1	FAULT IN 4SB OF MABC OR BBC738* INPUT TO MBCO61 S@1 IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES ITEST_SET_FAULT_1210000000011A1A1A121+22)	
			PUNCH TAPE LEADER 12 INCHES LONG	
			INITIALIZE DEFINE SELF TEST TAPE SET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST NCU CLOCK MODE (GTCOO3*) ENABLE LOW LEVEL ON GTCOO1* BRANCH TO MAJOR 29 MINOR 3	
29 01			STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
2 <b>9 02</b>	2	F31.3	CBC436* SƏ1 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I <u>INDICATORS</u> I DISPLAY.I.REPLACE ASSEMBLIES IND GO	
29 03 29 04	1	T1 01	TEST DATA INPUT TO DIHR FOR SƏL, ROM=A0000000->DIHR* DR->MTW2 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A00000 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFF0FEF COMPARE THE B REGISTER TO AFFFE BRANCH TO MAJOR 29 MINOR 5 ON NO-GO BRANCH TO MAJOR 29 MINOR 8	MTW2->RIM
29 05 29 06	2	T101.N	ISOLATE FAULT IN DATA INPUT TO DIHR BETWEEN LCU & SCU Logically *and* C register and aood7 - result in B & C register Branch to Major 29 Minor 7 on NO-GO	
	3	F101.NG	DATA INPUT TO LCU SECTION OF DIHR SØ1 Enable vertical parity check Stop Tape, display C register, nd-go light on	

TESTIDECISI	ON   TEST/FAULT LLNUMBER	SELF-TEST PROGRAM	I REMARKS
		IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES	
29 07 3	F101.NN	CATA INPUT TO SCU SECTION OF DIHR SƏL ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		I INDICATORS I DISPLAY I REPLACE ASSEMBLIES	- - -
29 08 1	T102	TEST CFLG* DR -> MTW2, DR ACTIVE	
29 09		SIGNAL ROUTING: GTC012* -> QUB000 SET THE SERIAL INPUT DATA FLAG (GTC012*) INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFF0FEF COMPARE THE B REGISTER TO A	MTW2->RIM
		LOGICALLY "AND" C REGISTER AND A00002 - RESULT IN B & C REGISTER BRANCH TO MAJOR 29 MINOR 10 ON NO-GO BRANCH TO MAJOR 29 MINOR 13	MASK OFF OTHER REC INPUTS
29 10 2 29 11	T102.N	TEST GTC012# ~> NTW1 (QUT011) INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OF9FFF0FFF COMPARE THE B REGISTER TO A LOGICALLY 'AND' C REGISTER AND A002 ~ RESULT IN B & C REGISTER BRANCH TO MAJOR 29 MINOR 12 ON NO-GO	MTW1->INMX
3	F102.NG	QUB000 OF MTW2 REC IS SƏ1 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		I <u>INDICATORS I DISPLAY I</u> <u>REPLACE ASSEMBLIES</u> IND GOI <u>BLANK IZA1A2A22</u>	_! _!
29 12 3	F102.NN	FAULT IN SSID IBT OR LATCH ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		IINDICATORSI_DISPLAYI	 _
29 13 1 29 14	T103	TEST RESET OF GTC012* WITH RSID RESET THE SERIAL INPUT DATA FLAG (GTC012*) INITIATE SELF TEST MODE 1~LOAD SELF TEST REGISTER WITH OFBFFF0FEF COMPARE THE B REGISTER TO A00002 LOGICALLY "AND" C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS	MTW2->RIM

	LEVEL 1	TEST/FAULT	SELF-TEST PROGRAM	REMARKS
			BRANCH TO MAJOR 29 MINOR 15 ON NO-GO Branch to Major 29 minor 16	
9 15 2	2 F1	103.N	RSID CAN NOT RESET GTC012* TO 1 Enable vertical parity check STOP TAPE, display c register, no-go light on	
			IINDICATORS I DISPLAY IREPLACE_ASSEMBLIES	}
9 16 1 9 17	1 Τ:	104	TEST DIHR* DR -> DOWD, DR INACTIVE LOAD A REGISTER WITH AFFFFF INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFF0FDF COMPARE THE B REGISTER TO A0018 LOGICALLY "AND" C REGISTER AND ACD88F - RESULT IN 8 & C REGISTER BRANCH TO MAJOR 29 MINOR 18 ON NO-GO BRANCH TO MAJOR 29 MINOR 23	DOWD & MDPL -> RIM Test only XTD->QUD&IOD
918 919	2 T	104 <b>.</b> N	TEST FOR FAULT IN 28V->LEVEL CONVERTERS FROM WTD013 Compare the B register to ACCBOF Branch to Major 29 Minor 20 on NO-Go	
:	3 F.	104.NG	28V SWITCH WTDO13 ACTIVE ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I <u>INDICATORS I DISPLAY I REPLACE ASSEMBLIES</u> IND GO I BLANK [2A1A2A07 I I2A1A3A26	
9 20 ÷	3 F	1 04. NN	SINGLE BIT FAULT IN DOWD REC, IODXXX ACTIVE OR QUD00(1,2) INACTIVE. SET UPERROR BIT COMPARE THE B REGISTER TO A ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
			INDICATORS         I         DI SPLAY         I         REPLACE         ASSEMBLIES           INO GO         I         10000000001241424(19,25)         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I         I	100121
			NO GO [ 40000000]2A1A2A(19,25) 	100021
			IND GD I 40000000[2A1A2A(19,24) I I2A1A3A26	I 0D009
			╵ <del>┍┍╤╤╘╗╗╗╝╔╝╖╗╧<u>┍</u>┟┍┍┍┍┍┍┍┍┍┍┍┍┍┍┍┍┍┍┍┍┍┍┍┍┍┍┍┍┍┍┍┍┍┍┍</del>	•

TESTIDECISION		 _}	SELF-1EST	「 PROGRAM 	REMARKS
		Т	ABLE_CONTINUE	D_FROM_PRECEEDING_PAGE	
		I NO_GO		2A1A2A(19.24)	100006
		IND GO	2000001	2A1A2A(19,24)	1 100005
		I		L2A1A3A26	I
		IND_GO		241424(19.24)	I I 0D004
		NO_60		2A1A2A(19.23)	1 100003
		INO_GO		24142423	QUD002
		1 <u>N0_G0</u>			QUD001   QUM904
		INO GO		2 A1 A2 A22   2 A1 A3 A29	
		NO GO		2 A1 A2 A22	 I QUM903
		1.0 00	•	12 A1 A3 A29	
		NO GO		2A1A2A22	1 QUM902
				2 41 43 430	
		IND GO	400	2A1A2A22	QUM901
		1	Ll	L2A1A3A30	1
9 21		SPARE			
9 22		SPARE			
				_	
9 23 1	T105	TEST DIHR* DR -> DOWD RE			
9 24		LOAD DISCRETE INPUT WO		F TEST REGISTER WITH OFBFFF0FDF	DOWD & MOPL -> RIM
		COMPARE THE B REGISTER		F TEST REGISTER WITH OFDEFFORDE	DOWD & HOPE - / KIM
				BBF - RESULT IN B & C REGISTER	TEST ONLY XTD->QUD&IOD
		BRANCH TO MAJOR 29 MIN			
		BRANCH TO MAJOR 29 MIN	OR 31		
0.05.0	T105 N	TECT COD INACTINE 204 CH	1764		
9 25 2	T105.N	TEST FOR INACTIVE 28V SW LOAD DISCRETE INPUT WO		TODEL HITH ACCES	
926		COMPARE THE B REGISTER		VUVL/ HIIN AFFFE	
				BAF - RESULT IN B & C REGISTER	TEST ONLY XTD->QUD&IOD
		BRANCH TO MAJOR 29 MIN			
	_				
3	F105.NG	28V SWITCH WTD013 INACTI			
		ENABLE VERTICAL PARITY STOP TAPE, DISPLAY C R		CO 1 1 CHT ON	
		STOP TAPE, DISPLAT C R	EGISTER, NU-		
		IINDICATORS	DISPLAY	REPLACE ASSEMBLIES	
		IND GO		2 A1 A2 A07	(
		1		2A1A3A26	I
		ł		OR	1
		I	Ll	LPOWER_SUPPLY_(PARA_3-21)	1
9273	F105.NN	SINGLE BIT FAULT IN DOWD	REC. IODXXX	INACTIVE OR QUDOO(1,2) ACTIVE.	SET
		UP ERROR BIT			
		ENABLE VERTICAL PARITY	CHECK		
		INITIATE SELF TEST MOD	E 1-LOAD SELF	F TEST REGISTER WITH OFBFFFOFDF	DOWD&MDPL->RIM
		COMPARE THE B REGISTER	TO ACOROR		
			TO ACDEOF		

*****	**************************************	
TESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
I NO. L LEVEL L NUMBER L		
, ************************************		

#### LOGICALLY 'AND' C REGISTER AND ACD88F - RESULT IN 8 & C REGISTER STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON

I_INDICATORS	I DI SPLAY I REPLACE ASSEMBLIES	
IND GO	100000000 2A1A2A(19,25)	TOD121
l	<u>112A1A3A26</u>	1
IND GO	40000000 2A1A2A(19,25)	I GD 0 2 1
!	_112A1A3A26	
IND GO	4000000 2A1A2A(19,24)	1 IOD009
	<u>l2a1A3A26</u>	1
NO GO	2000000 2A1A2A(19,24)	IOD008
I	<u> </u>	1
NO_GO	1400000012A1A2A(19,24)	I 0D006
NO GO	2000000/2A1A2A(19,24)	1 100005
I	I2A1A3A26	1
1 NO_GO	100000012A1A2A(19,24)	I 0D004
1NO_GO	140000012A1A2A(19.23)	I IOD003
1 NO_GO	120000012A1A2A23	
INO. GO	1 100000124142423	000001
NO GO	4000/24142422	QUM904
1	1 12 A1 A3 A29	1
IND GO	2000/2A1A2A22	QUM903
1	112 A1 A3 A29	1
IND GO	1 1000  2A1A2A22	1 QUM902
I	112A1A3A30	1
IND GO	40012A1A2A22	UM901
I	I2A1A3A30	1

29 28	SPARE
29 29	SPARE
29 30	SPARE

29 31	1	T1 06	TEST DIHR* DR -> JEA*, DR ACTIVE	
29 32			INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBEFFOFFF	JEA->RIM
			COMPARE THE B REGISTER TO ADDFFC	
			LOGICALLY 'AND' C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS	MASK OFF OTHER REC
			BRANCH TO MAJOR 29 MINOR 33 ON NO-GO	
			BRANCH TO MAJOR 29 MINOR 39 _	

29 33	2	T106.N	TEST FOR JEA* REC EN SOO
29 34			COMPARE THE B REGISTER TO ADOFFC
			BRANCH TO MAJOR 29 MINOR 35 ON NO-GO

3 F106.NG JEA\* REC EN SÃO - ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON

TESTIDE		TEST/FAULT	I SELF-TEST PROGRAM	1 R EMARKS
			I INDICATORS I DISPLÀY I REPLACE ASSEMBLIES I IND.GO	
2935	3 F	106.NN	SINGLE BIT OF JEA* REC INACTIVE, SET UP ERROR BIT ENABLE VERTICAL PARITY CHECK COMPARE THE B REGISTER TO A STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
			IND_GDI       40000 [1 A1 A4 A07       I         IND_GDI       20000 [1 A1 A4 A1 5 • 8]       I         IND_GDI       10000 [1 A1 A4 A1 5 • 8]       I         IND_GDI       40001 1 A1 A4 A1 5 • 8]       I	IUA140 IUA139 IUA138 IUA137 IUA136 IUA135 IUA135 IUA133 IUA132 IUA131
29 36 29 37 29 38			SPARE SPARE SPARE	
29 39 3 29 40	1 †	107	TEST DIHR* DR -> JEA*, DR INACTIVE LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A000000 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBEFFOFFF COMPARE THE B PEGISTER TO A LOGICALLY 'AND' C REGISTER AND A00FFC - RESULT IN B & C REGISTER BRANCH TO MAJOR 29 MINOR 41 ON NO-GO BRANCH TO MAJOR 29 MINOR 44	JEA->RIM
29 41 7	2 F	107.N	ND_GDI10000011A1A4A071	IUA140 IUA139 IUA138 IUA137 IUA136 IUA135

TESTIDECISION	TEST/FAULT 1NUMBEB	SELF-TEST PROGRAM	I REMARKS
		TABLE_CONTINUED_FROM_PRECEEDING_PAGE         IND_GD       2000011A1A4A15.81         IND_GD       1000011A1A4A15.81         IND_GD       1000011A1A4A14.81         IND_GD       200011A1A4A14.81	_  IUA134 _  IUA133 _  IUA132 _  IUA132 _  IUA131
9 42 9 43		SP AR E SP AR E	
29 44 1 29 45	T108	CFLG* DR -> MTW1 REC, DR INACTIVE RESET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST CIU CLOCK MODE (GTC003*) LOAD A REGISTER WITH AF INITIATE SELF TEST MODE 1-LOAD SELF TE\$T REGISTER WITH OF9FFF0FFF COMPARE THE B REGISTER TO AFFFFF2 SET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST NCU CLOCK MODE (GTC003*) BRANCH TO MAJOR 29 MINOR 46 ON NO-GO BRANCH TO MAJOR 29 MINOR 56	MTW1->INMX
29 46 2	T108.N	TEST FOR MTW1 REC EN S@O Compare the B register to A03FFF2 Branch to Major 29 Minor 47 on ND-GO	
3	F108.NG	MTW1 REC EN SOO ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I <u>INDICATORS I DISPLAY I REPLACE ASSEMBLIES</u> IND.GO	_ _1 _1
29 47 3	T1 08. NN	TEST FOR MTW1 REC EN SOO Compare the B register to Afcoff Branch to Major 29 Minor 48 on ND-Go	
4	F108.NNG	MTW1 REC EN S@O ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I <u>INDICATORS I DISPLAYI REPLACE ASSEMBLIES</u> IND_GOIBLANKI1A1A4A2O	<u>-</u>
29 48 4	T108.NNN	TEST FOR MTW1 REC EN SOO Compare the B register to Afffoo2 Branch to Major 29 Minor 49 On NO-Go	

ITESTID		TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
	5	F108.NNNG	MTW1 REC EN SOO ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
			NO_GOIBLANKI1A1A4A2QI	
29 49	5	T108.NNNN	TEST FOR CFLG* DR EN SØ1 Compare the B register to Alffff2 Branch to Major 29 Minor 50 on NO-GO	
	6	F108.NNNNG	ITW151 SQO ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON	
			I INDICATORS I DISPLAY I REPLACE ASSEMBLIES	
29 50	6	T108.NNNNN	TEST FOR CFLG* DR EN S&1 Compare The B register to A1FFBF2 Branch to Major 29 Minor 51 on NO-Go	
	7	F108.NNNNN >G	KMVO11* SƏO ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
			INDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI INO_GOIBLANKIIAIA3A06I	
29 51	7	T108.NNNNN >N	TEST FOR CFLG* DR EN SƏ1 Compare The B register to Affffc2 Branch to Major 29 Minor 52 on ND-Go	
	8	F108.NNNNN >NG	CTW114* SQO ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT DN	

200

ITESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS I
I_NO_ILEVELLNUMBERI		L

I INDICATORS I DIG		OFOLACE ACCEMOLT	te i
I_INDICATORSI_DIS		RELIACE ADDEDDIT	<u> </u>
IND GO	KLANK ELAIAZA()	4	
· · · · · · · · · · · · · · · · · · ·			

- 29 52 8 T108.NNNNN --->NN CHECK FOR FAULT IN GTC021\*->QUT016 COMPARE THE B REGISTER TO AFFFEF2 BRANCH TO MAJOR 29 MINOR 53 ON ND-GO
  - F108.NNNNN --->NNG ENABLE VERTICAL PARITY CHECK FAULT IN GTCO21\*->QUT016. TEST FOR ACTIVE CMA145 SERIALLY LOAD THE B REGISTER WITH AFFFFFF INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF1F1F0FFF SINGLE READ MEMORY MODE-READ MB LINES-ADDRESS 0 COMPARE THE B REGISTER TO A04 LOGICALLY 'AND' C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON

MTW1->INMX->BREG ON BMA165\*

INDICATORS	1 DI SPLAY		ESI
ING GO	BL ANK	1 1A1A2A(9, 10, 11, 16)	CMA145 NOT AT FAULT
l	1	1 A1 A3 A03	1
I	1	<u></u>	<u></u>
INO GO	12000000	Q <u> 1A1A3A(1+3)</u>	CMA145 ACTIVE

#### 29 53 9 F108.NNNN

--->NNN

9

SINGLE BIT OF CFLG\* DR ACTIVE OR MTW1 REC INACTIVE. SET UP ERROR BIT ENABLE VERTICAL PARITY CHECK COMPARE THE B REGISTER TO AFFFFF2 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON

INDICATORS	I DISPLAY I REPLACE ASSEMBLIES	
IND GO	1 1000000000 (1 A1 A2 A (12,13)	GTA000* OR QUT001 500
1	<u> </u>	1
NO GO	40000000011A1A2A(12,13)	I GTEOOO* DR QUTOO2 Sao
1	_i	1
IND GO	2000000011A1A2A(12,13)	I GTI000* OR QUT003 Sao
1	_1I1A1A4A10	1
1 NO_GO	14000000011A1A3A01	KMA051* S20
NO GO	100000000 1A1A2A(12,13,19)	GTP000* OR QUT004 Sa0
1	<u>1 11114410</u>	1
IND GO	4000000011A1A2A(13,15,19)	GTM010# DR QUT005 Sa0
I	_1 <u>_11A1A4A10</u>	1
IND GO	2000000011A1A2A(10,11,13)	I GTBODO* DR QUTOO6 SOO
1	_111A1A4A09	1
	TABLE CONTINUED ON FOLLOWING PAGE	

TABLE CONTINUED ON FOLLOWING PAGE

ITESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS I
I_NO.1_LEVEL_1NUMBER1		

	TABLE CONTINUED FROM PRECEEDING PAGE	_
NO GO	10000000 1A1A2A(9,10,16)	GTC002* DR QUT007 Sa0
	<u>ii1A1A4A09</u>	_1
NO GO	4000000 1A1A2A10	GTC003* DR QUT008 Sa0
	<u>    A  A4A09</u>	_1
NO GO	2 000000   1 A1 A4 A08	GTC010* OR QUT009 Sa0
	II2A1A2A17	_1
NO_GO	1 10000001PROCEED PER PARAGRAPH 3-12D	_  GTC011* ACTIVE OR QUT010 Sa0
NO_GO	1 40000011A1A4A08	4 QUT011 Sao
NO GO	20000011A1A3A(2,9)	GTC013* OR QUT012 Sa0
	I IIAIA4A07	_1
NO GO	100000/1A1A2A(6,11,12,16)	I GTC014+ DR QUT013 Sa0
· · · ·	1I1A1A4A07	_1
NO GO	40000 1A1A2A(11,14,16)	I GTC020* OR OUT014 Sa0
	1 114144407	_1
NO GO	4000 1A1A2A(10,11,17)	I GTC022+ OR QUT017 Sa0
	11 A1 A3 A03	1
	II1A1A4A04	_i
NO GO	2000 14143402	I GTWOO1+ OR QUTO18 SOO
	I	1
NO GO	1 1000 1A1A2A(10,14)	
	I I 1 A 1 A 4 A 0 4	1
	1I1A1A2A04	i
NO GO	400 1A1A2A(10,14)	T XTW136* OR QUT020 Sa0
	1 11144403	
1		i
1	I	

#### 29 54 29 55 SPARE SPARE

29 56	1	T1 09	TEST QJD DR -> EXMW REC, ROM = A0000000 & DR INACTIVE	
			SIGNAL ROUTING:	
			XTQ021 -> QUM043	
			XTQ022 -> QUM042	
			XTQ023 -> QUM040	
29 57			LOAD A REGISTER WITH AO	
			RESET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST CIU CLOCK MODE	
			(GTC003*)	
			INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBEFFOFFF	WD3&JEA&EXMW->INMX
			COMPARE THE B REGISTER TO A	
			LOGICALLY 'AND' C REGISTER AND A0000034 - RESULT IN B & C REGISTER	
			BRANCH TO MAJOR 29 MINOR 58 ON NO-GO	
			BRANCH TO MAJOR 29 MINOR 62	

29 58 2 T109.N TEST FOR QJD DR EN Sal 29 59 COMPARE THE B REGISTER TO A0000034 BRANCH TO MAJOR 29 MINOR 60 ON NO-GO

TESTIDECISION	TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
3	F109.NG	QJD DR EN SƏ1 SET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST NCU CLOCK MODE (GTC003*) ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSL_DISPLAY1	- _1 _1
9603	F109.NN	SINGLE BIT OF XTQ -> QUM SƏ1. SET UP ERROR BIT ENABLE VERTICAL PARITY CHECK SET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST NCU CLOCK MODE (GTC003*) COMPARE THE B REGISTER TO A STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON	
		INDICATORS       I DISPLAY       I       REPLACE ASSEMBLIES         IND GO       I       40 1A1A4A02         I       I2A1A2A(I3.26)         IND GO       I       20 1A1A4A02         I       I2A1A2A(I3.26)         IND GO       I       20 1A1A4A02         I       I2A1A2A(I3.26)         IND GO       I       20 1A1A4A02         I       I2A1A2A(I3.26)         IND GO       I       4 1A1A4A01         I       I2A1A2A(I3.26)	XTQ021 OR QUM043   XTQ022 OR QUM042   XTQ023 OR QUM040   XTQ023 OR QUM040
9 61		SPARE	
29621 2963	τ110	TEST FOR QJD HOLDING REG EN SƏ1 LOAD A REGISTER WITH AF INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBEFFOFFF COMPARE THE B REGISTER TO A LOGICALLY 'AND' C REGISTER AND A0000034 - RESULT IN B & C REGISTER SET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST NCU CLOCK MODE (GTC003*) BRANCH TO MAJOR 29 MINOR 64 ON NO-GO BRANCH TO MAJOR 29 MINOR 68	WD3&JEA&EXMW->INMX
29642	F110.N	FAULT IN QJD HOLDING REG DATA DEPENDENT ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES IND_GOIXXI2AIA2AI3	 _ 1
29 65 29 66 29 67		SPARE SPARE SPARE	
29 68 1	<b>T</b> 111	TEST QJD DR'-> EXMW REC, DR ACTIVE	

		TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
9 69			SIGNAL ROUTING: XTQ021 -> QUM043 XTQ022 -> QUM042 XTQ023 -> QUM040 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBEFF8FFF COMPARE THE B REGISTER TO A0000034 LOGICALLY 'AND' C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS BRANCH TO MAJOR 29 MINOR 70 ON ND-GO BRANCH TO MAJOR 29 MINOR 76	1->QJD, EXM₩->INMX
29 70 29 71	2	T111.N	TEST FOR QJD DR EN SØO Compare the B register to A0000034 Branch to Major 29 Minor 72 on NO-Go	
	3	F111.NG	QJD DR EN SØO ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYI	1
29 72	3	F111.NN	SINGLE BIT OF XTQ -> QUM S@O. SET UP ERROR BIT         ENABLE VERTICAL PARITY CHECK         COMPARE THE B REGISTER TO A         STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON         I	   XTQ021 OR QUM043   XTQ022 OR QUM042   XTQ023 OR QUM040
29 73 29 74 29 75			SPARE SPARE SPARE	
	* * *	*****	TEST FOR SHORTS IN EXTERNAL DATA PATHES T112 - T121 MINOR 76 - 98	************* * *
29 76	*	**************************************	TEST FOR SHORT IN WD1* -> PJB	*****
	-		LOAD A REGISTER WITH A88888888 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 8FBFFF0FF7	ROM->WD1, PJB->RIM

TESTIDECISION   TEST ND.1 LEVEL 1 N	T/FAULT	SELF-TEST PROGRAM	I REMARKS
		COMPARE THE B REGISTER TO A777777 Branch to major 29 ∺Inor 87 on no-go	
		LOAD A REGISTER WITH A4444444 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 8FBFFF0FF7 COMPARE THE B REGISTER TO ABBBBBBB BRANCH TO MAJOR 29 MINOR 87 ON NO-GO	ROM->WD1, PJB->RIM
		LOAD A REGISTER WITH A2222222 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 8FBFFF0FF7 COMPARE THE B REGISTER TO ADDDDDDD BRANCH TO MAJOR 29 MINOR 87 ON NO-GO	ROM->WD1, PJB->RIM
		LOAD A REGISTER WITH A1111111 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 8FBFFF0FF7 COMPARE THE B REGISTER TO AEEEEEEE BRANCH TO MAJOR 29 MINOR 87 ON NO-GO	ROM->WD1, PJ8->RIM
		LOAD A REGISTER WITH A5A5A5A5 Initiate self test mode 1-load self test register with 8fbfffoff7 Compare the B register to AA5A5A5A Branch to Major 29 Minor 87 on No-go	ROM->WD1, PJB->RIM
		LOAD A REGISTER WITH AFFOOFFO Initiate SELF test mode 1-load self test register with 8FBFFFOFF7 Compare the 8 register to A00FFOOF Branch to major 29 minor 87 on NO-go	ROM->WD1, PJB->RIM
		LOAD A REGISTER WITH A00FFFF0 Initiate self test mode 1-load self test register with 8FBFFF0FF7 Compare the B register to Aff0000F Branch to major 29 minor 87 on NO-G0	ROM->WD1, PJ8->RIM
		-	
977 1 113		TEST FOR SHORT IN WD1* -> NAD* LOAD A REGISTER WITH A88888888 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 878FF0FFF COMPARE THE B REGISTER TO A88888888 BRANCH TO MAJOR 29 MINOR 88 ON NO-GO	ROM->WD1, NAD->INMX
		LOAD A REGISTER WITH A4444444 Initiate self test mode 1-load self test register with 87BFFF0FFF Compare the 8 register to A4444444 Branch to major 29 minor 88 on no-go	ROM->WD1, NAD->INMX
		LOAD A REGISTER WITH A2222222 Initiate Self test mode 1-load self test register with 878FFF0FFF Compare the B register to A2222222 Branch to major 29 minor 88 on ND-go	ROM->WD1, NAD->INMX
		LOAD A REGISTER WITH A1111111 Initiate Self test mode 1-load self test register with 878ffofff Compare the B register to A1111111 Branch to Majop Minor 88 on ND-GO	ROM>WDI; NAD->INMX

ESTIDECISION	TEST/FAULT	I SELF-TEST PROGRAM	REMARKS
		LOAD A REGISTER WITH A5A5A5A5 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 878FFF0FFF Compare the B register to A5A5A5A5 Branch to Major 29 Minor 88 ON NO-GO	ROM->WD1, NAD->INMX
		LOAD A REGISTER WITH AFFOOFFO INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 87BFFFOFFF Compare the B register to Affooffo Branch to Major 29 Minor 88 ON NO-GO	ROM->WD1, NAD->INMX
		LOAD A REGISTER WITH A00FFFF0 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 87BFFF0FFF Compare the B register to A00FFFF0 Branch to Major 29 Minor 88 ON NO-GO	ROM->WD1, NAD->INMX
78 1	T114	TEST FOR SHORT IN MB -> JEB LOAD A REGISTER WITH A88888888 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 288FFF0FFF Compare the B register to A88888888 BRANCH TO MAJOR 29 MINOR 89 ON NO-GO	ROM->MB, JEB->INMX
		LOAD A REGISTER WITH A4444444 Initiate self test mode 1-load self test register with 288FFF0FFF Compare the B register to A4444444 Branch to Major 29 minor 89 on NO-GO	ROM->MB, JEB->INMX
		LOAD A REGISTER WITH A2222222 Initiate self test mode 1-load self test register with 288fff0fff Compare the 8 register to A2222222 Branch to major 29 minor 89 on NO-go	ROM->MB, JEB->INMX
		LOAD A REGISTER WITH A1111111 Initiate self test mode 1-load self test register with 2bbfffofff Compare the B register to A1111111 Branch to major 29 minor 89 on ND-gd	ROM->MB, JEB->INMX
		LOAD A REGISTER WITH A5A5A5A5 Initiate self test mode 1-load self test register with 2bbfffofff Compare the B register to A5A5A5A5 Branch to major 29 minor 89 on No-go	ROM->MB, JEB->INMX
		LOAD A REGISTER WITH AFFOOFFO Initiate self test mode 1-load self test register with 288FFFOFFF Compare the 8 register to AFFOOFFO Branch to major 29 minor 89 on NO-GO	ROM->MB, JEB->INMX
		LOAD A REGISTER WITH A00FFFF0 Initiate self test mode 1-load self test register with 2bbfff0fff Compare the 8 register to A00ffff0 Branch to major 29 minor 89 on NO-g0	ROM->MB, JEB->INMX

29 79 1 T115 TEST FOR SHORT IN XMB\* -> FMB

ITESTIDECISION	TEST/FAULT   NUMBERL	SELF-TEST PROGRAM	REMARKS
		LOAD A REGISTER WITH A88888888 Initiate self test mode 1-load self test register with 1fbbffofff Compare the B register to A777777 Branch to Major 29 Minor 90 on NO-go	ROM->XMB, FMB->INMX
		LOAD A REGISTER WITH A4444444 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 1FBBFF0FFF Compare the B register to Abbbbbbb Branch to Major 29 Minor 90 on NO-go	ROM->XMB. FMB->INMX
		LOAD A REGISTER WITH A2222222 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 1FBBFF0FFF Compare the B register to addddddd Branch to Major 29 Minor 90 on No-go	ROM->XMB, FMB->INMX
		LDAD A REGISTER WITH A1111111 Initiate self test mode 1-load self test register with 1f8bffofff Compare the B register to aeeeeee Branch to major 29 Minor 90 on NO-go	ROM->XMB, FMB->INMX
		LOAD A REGISTER WITH A5A5A5A5 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 1FBBFF0FFF Compare the B register to AA5A5A5A Branch to Major 29 Minor 90 on NO-GO	ROM->XMB, FMB->INMX
		LOAD A REGISTER WITH AFFOOFFO Initiate self test mode 1-load self test register with 1fbbffofff Compare the B register to Aooffoof Branch to major 29 minor 90 on NO-go	ROM->XMB, FMB->INMX
		LOAD A REGISTER WITH AOOFFFFO Initiate self test mode 1-load self test register with 1fbbffofff Compare the B register to affo000f Branch to major 29 minor 90 on ND-go	ROM->XMB, FMB->INMX
29 80 1	T116	TEST FOR SHORT IN XMB# -> XMB* LOAD A REGISTER WITH A88888888 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 1FBDFF0FFF COMPARE THE B REGISTER TO A88888888 BRANCH TO MAJOR 29 MINOR 91 ON NO-GO	ROM->XMB, XMB->INMX
		LOAD A REGISTER WITH A4444444 Initiate self test mode 1-load self test register with 1fbdffofff Compare the B register to A4444444 Branch to major 29 Minor 91 on ND-Go	ROM->XMB, XMB->INMX
		LOAD A REGISTER WITH A2222222 Initiate self test mode 1-load self test register with 1fbdffofff Compare the B register to A2222222 Branch to major 29 Minor 91 on ND-GO	ROM->XMB, XMB->INMX
		LOAD A REGISTER WITH A1111111 Initiate self test mode 1-load self test register with 1FBDFFOFFF	ROM->XMB, XMB->INMX

TESTIDECISION	I TEST/FAULT	I SELF-TEST PROGRAM	REMARKS
		COMPARE THE 8 REGISTER TO A1111111 Branch to Major 29 Minor 91 on ND-Go	
		LOAD A REGISTER WITH A5A5A5A5 Initiate self test mode 1-load self test register with 1fbdffofff Compare the B register to A5A5A5A5 Branch to Major 29 Minor 91 on NO-GO	ROM->XNB, XMB->INMX
		LOAD A REGISTER WITH AFFOOFFO INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 1FBDFFOFFF Compare the B register to Affooffo Branch to Major 29 Minor 91 on ND-Go	ROM->XMB, XMB->INMX
		LOAD A REGISTER WITH AOOFFFFO Initiate self test mode 1-load self test register with 1fbdffofff Compare the B register to Aooffffo Branch to major 29 minor 91 on ND-GO	ROM->XMB, XMB->INMX
981 1	T117	TEST FOR SHORT DIHR* -> MTW2 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A88840 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFF0FEF COMPARE THE B REGISTER TO A77774 LOGICALLY 'AND' C REGISTER AND FFFFF4 - RESULT IN B & C REGISTER BRANCH TO MAJOR 29 MINOR 92 ON NO-GO	MTW2->RIM
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A44420 Initiate self test mode 1-load self test register with ofbfffofef Compare the B register to Abbbb4 Logically 'And' C register and Fffff4 ~ result in B & C register Branch to major 29 Minor 92 on NO-GO	MTW2->RIM
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A22210 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFFOFEF Compare the B register to Addddo Logically 'And' C register and FFFF4 - Result in B & C register Branch to Major 29 Minor 92 on NO-GO	MTW2->RIM
		LOAD DISCRETE-INPUT WORD (EIP/EOP CODE) WITH AllIOB INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFF0FEF Compare The B register to Aeeee4 Logically "And" C register and FFFFF4 - Result in B & C register BRANCH TO MAJOR 29 MINOR 92 ON ND-GO	MTW2->RIM
		LOAD DISCRETE INPUT WORD (EIP/50P CODE) WITH A48220 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OF8FFF0FEF Compare the B register to Ab70b0 Logically 'And' C register and FFFFF4 - result in B & C register Branch to major 29 Minor 92 on NO-GO	MTW2->RIM
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A84118 Initiate self test mode 1-load self test register with ofbfffofef Compare the B register to Atbec4 Logically 'And' C register and fffff4 - result in B & C register	MTW2->RIM

TESTIDECISION   NO.1 LEVEL		SELF-TEST PROGRAM '	I REMARKS
		BRANCH TO MAJOR 29 MINOR 92 ON ND-GO LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A12800 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFFOFEF COMPARE THE B REGISTER TO AEDF74 LOGICALLY 'AND' C REGISTER AND FFFFF4 - RESULT IN 8 & C REGISTER BRANCH TO MAJOR 29 MINOR 92 ON NO-GO	MTW2->R IM
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A21440 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFF0FEF COMPARE THE'B REGISTER TO ADE3F4 LOGICALLY 'AND' C REGISTER AND FFFFF4 - RESULT IN B & C REGISTER BRANCH TO MAJOR 29 MINOR 92 ON ND-GO	MTW2->RIM
9821	T118	TEST FOR SHORT IN INVERTED DOWD LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A0010 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFFOFDF COMPARE THE B REGISTER TO A01 LOGICALLY 'AND' C REGISTER AND A016 - RESULT IN B & C REGISTER BRANCH TO MAJOR 29 MINOR 93 ON NO-GO	DOWD->RIM
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A0004 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFF0FDF Compare the B register to A004 Logically 'AND' C register AND A016 - Result in B & C register Branch to Major 29 Minor 93 on NO-GO	DOWD->R IM
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A0002 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFF0FDF COMPARE THE B REGISTER TO A002 LOGICALLY 'AND' C REGISTER AND A016 - RESULT IN B & C REGISTER BRANCH TO MAJOR 29 MINOR 93 ON NO-GO	DOWD->RIM
983 1	T119	TEST FOR SHORT IN IUAXXX OF JEA REC LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A924 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBEFFOFFF COMPARE THE 8 REGISTER TO A00924 LOGICALLY "AND" C REGISTER AND A00FFC - RESULT IN B & C REGISTER BRANCH TO MAJOR 29 MINOR 94 ON NO-GO	JEA->INMX
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A490 Initiate self test mode 1-load self test register with ofbeffofff Compare the B register to A00490 Logically "And" C register and A00ffC - Result in B & C register Branch to Major 29 minor 94 on NO-GO	JEA->INMX
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A248 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBEFFOFFF Compare the B register to A00248 Logically 'And' C register and A00FFC - result in B & C register Branch to Major 29 Minor 94 On NO~GO	JEA->INMX

ND_1_LEVEL	TEST/FAULT	I SELF-TEST PROGRAM	I RENARKS
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A2AO INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBEFFOFFF Compare the B register to A002AO Logically 'AND' C register and A00FFC - Result in B & C register BRANCH TO MAJOR 29 MINOR 94 ON NO-GO	JEA-> INMX
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A508 Initiate Self test mode 1-load Self test register with ofbeffofff Compare the B register to A00508 Logically 'And' C register and A00FFC - result in B & C register Branch to Major 29 Minor 94 on NO-GO	JEA->INMX
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A850 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBEFFOFFF Compare the B register to A00850 Logically "And" C register and A00FFC ~ Result in B & C register BRANCH to Major 29 Minor 94 on ND-GO	JEA->INMX
984 1	1 1120	TEST FOR SHORT IN CM+ -> WD3 & EXMW LOAD A REGISTER WITH AA50 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 4FBEFFOFFF COMPARE THE B REGISTER TO A5A001 LOGICALLY 'AND' C REGISTER AND AFF001 ~ RESULT IN B & C REGISTER BRANCH TO MAJOR 29 MINOR 95 ON NO-GO	ROM->CM, WD3&EXMW->INMX
		LOAD A REGISTER WITH A5A0 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 4FBEFFOFFF Compare the B register to AA5001 Logically 'And' C register and Affo01 ~ result in B & C register Branch to Major 29 Minor 95 on NO-GD	ROM->CM, WD3&EXMW->INMX
		LOAD A REGISTER WITH A990 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 4FBEFFOFFF Compare the B register to A66001 Logically 'And' C register and Affo01 - Result in B & C register Branch to Major 29 Minor 95 on NO-GO	ROM->CM, WD3&EXMW->INMX
		LOAD A REGISTER WITH A008 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 4FBEFF0FFF Compare the B register to AFF Logically "And" C register and Aff001 - result in B & C register Branch to major 29 Minor 95 on ND-G0	RON->CN, WD3GEXMW->INMX
9851	T121	TEST FOR SHORT IN IUMXXX OF JCM* REC LOAD A REGISTER WITH AA50 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 4FAFFFOFFF Compare the B register to AA5 BRANCH TO MAJOR 29 MINOR 96 ON NO-GO	ROM->CM, JCM->INMX
		LOAD A REGISTER WITH A5A0 Initiate self test mode 1-load self test register with 4fafffofff Compare the B register to A5A	ROM->CM, JCM->INMX

	ON   TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
		BRANCH TO MAJOR 29 MINOR 96 ON NO-GO	
		LOAD A REGISTER WITH A990 Initiate self test mode 1-load self test register with 4fafffofff Compare the B register to A99 Branch to Major 29 Minor 96 on ND-GO	ROM->CM, JCM->INMX
		LOAD A REGISTER WITH A008 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH 4FAFFF0FFF COMPARE THE B REGISTER TO A008 BRANCH TO MAJOR 29 MINOR 96 ON NO-GO	ROM->CM, JCM->INMX
		BRANCH TO MAJOR 29 MINOR 98	
29 86		SPARE	
29872	F112.N	SHORT IN WO1* -> PJB STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
29882	F113.N	SHORT IN IUD(131-158) STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
29892	F114.N	SHORT IN MB -> JEB STOP TAPE, DISPLAY C REGISTER, ND-GD LIGHT ON	
29902	F115.N	SHORT IN XMB* -> FMB STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
29912	F116.N	SHORT IN (TB(141- 168) STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
29922	F117.N	SHORT IN DIHR* -> MTW2 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
29932	F118.N	SHORT IN IODXXX OF DOWD REC STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
29 <del>9</del> 4 2	F119.N	SHORT IN IUAXXX OF JEA* REC STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON	
29 95 2	F120.N	SHORT IN CM+ -> WD3 & EXMW STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	

TESTICECISION   TEST/FAULT				
29 96 2 F121.N	SHORT IN IUMXXX OF JCM* REC STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON			
29 97	SPARE			
29 98 29 99	ENABLE VERTICAL PARITY CHECK END OF MAJOR TEST			

TESTICECISION	TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
: :	}************* :	***************************************	***************************************
1	k k	COMPUTER LOAD CONTROL TESTS	*
د ۲	k K	MAJOR 30 AND 31	*
1	***********	***************************************	******
0 00		INITIALIZE DEFINE SELF TEST TAPE Enable low level on gtcoo1* Branch to major 30 minor 3	
0 01		STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON	
0022	T30.5	FAULT IN ENABLE OF ROM Stop Tape, Display C register, NO-GO Light On	
		INDICATORS I DISPLAY I REPLACE ASSEMBLIES	- -  -
0 03 1	T125	TEST RESET OF TST2 WITH LQJD	
0 04		PREVIOUS TEST = (29)T121 Reset inhibit increment CP flag & enable self test ciu clock mode (gtc003*)	
		SERIALLY LOAD THE B REGISTER WITH AFFFFFF Initiate self test mode 2-load self test register with ofbfff4fff Enable af to the QJD lines	SIM NO-GD
2	F125.1	FAULT LOC WITHIN TEST T125, NOT A PROGRAMMED STOP- LQJD LATCH NOT RESET	
		INDICATORS I DISPLAY I REPLACE ASSEMBLIES	-1
1	T125(CONT)	BRANCH TO MAJOR 30 MINOR 6 ON NO-GO Branch to Major 30 minor 10	
10 05		SPARE	
0 06 2	F125.2	FAULT IN LQJD IBT OR LATCH, OR RESET OF TST2 Enable vertical parity check Stop Tape, display c register, ND-GO light on	

TESTIDECISION	I TEST/FAULT	I SELF-FEST PROGRAM	REMARKS
		INDICATORS 1 DISPLAY 1	
30 07 30 08 30 09		SPARE SPARE SPARE	
30 10 1 30 11	T126	TEST FOR LOAD OF B REG Compare the B register to A Branch to Major 30 Minor 13 On NO-GO Branch to Major 30 Minor 17	
30 12		SPARE	
30132	F126.N	INPUT TO GYR742 SƏ1 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I <u>INDICATORS</u> I <u>DISPLAY</u> I <u>REPLACE ASSEMBLIES</u> IND <u>GO</u> IIITTTTTTTTTTTTTLA1A3A15	
30 14 30 15 30 16		SPARE SPARE SPARE	
30 17 1 30 18	T127	TEST LOAD OF QJD HOLDING REG INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBEFFOFFF ENABLE AF TO THE QJD LINES COMPARE THE B REGISTER TO A0000034 LOGICALLY 'AND' C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS BRANCH TO MAJOR 30 MINOR 20 ON NO-GO BRANCH TO MAJOR 30 MINOR 24	EXMW->INMX, INMX->BREG OF RESET QJD
30 19		SPARE	
30202	F127.N	FAULT IN QJD HOLCING REG ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	

ITESTID		I TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
			IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI	
30 21 30 22 30 23			SPARE SPARE SPARE	
30 24 30 25	1	¥128	TEST FOR DATA INPUTS TO QJD HOLDING REG SƏ1 ENABLE A TO THE QJD LINES COMPARE THE E REGISTER TO A LOGICALLY 'AND' C REGISTER AND A0000034 - RESULT IN B & C REGISTER BRANCH TO MAJOR 30 MINOR 27 ON NO-GO BRANCH TO MAJOR 30 MINOR 31	
30 26			SPARE	
30 27	2	F128.N	CATA INPUT TO QJD HOLDING REG SƏ1 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I INDICATORS I DISPLAY I BEPLACE ASSEMBLIES	
30 28 30 29 30 30			SPARE SPARE SPARE	
30 31 30 32	1	T129	TEST "GEN LOAD" RESET OF TST2 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH 07BFFF4FFF SET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST NCU CLOCK MODE (GTC003*) PULSE CA DRIVERS WITH 0000007	NAD->INMX, INMX->BREG ON LOAD EN, SIM NO-GO
	2	F129.1	FAULT LOC WITHIN TEST T129, NOT A PROGRAMMED FAULT- LDCA LATCH NOT RESET	
	ı	T129(CONT)	BRANCH TO MAJOR 30 MINOR 33 ON NO-GO Branch to Major 30 minor 41	
30 33 30 34	2	T129.2	TEST LXMB ★> GEN LOAD RESET OF TST2 PULSE THE XMB DRIVERS WITH THE A REGISTER	

TESTIDECIS	ION   TEST/FAULT	SELF-TEST PROGRAM	REMARKS
		BRANCH TO MAJOR 30 MINOR 35 ON NO~GO	
3	F129.2.G	FAULT IN LDCA IBT, LATCH, OR GATING Enable vertical parity check Stop Tape, display c register, ND-GO light on	
		I INDICATORS I DISPLAY I REPLACE ASSEMBLIES	.)
30 35 3 30 36	Ť129.2.N	TEST CLEAR EN RESET OF TST2 SET THE I/O COMPLETE FLAG (GTC010*)	RESET TST2
		RESET THE I/O COMPLETE FLAG (GTCO10*) Initiate self test mode 2-load self test register with 0F3FFF4FFF Pulse ca drivers with the a register	SIM NO-GO, RESET TST2 ON CLEAR EN
		BRANCH TO MAJOR 30 MINOR 37 ON NO-GO	
4	F129.2.NG	FAULT IN GEN LOAD RESET OF TST2 Enable vertical parity check Stop tape, display c register, no-go light on	
		I INDICATORS I DISPLAY I REPLACE ASSEMBLIES NO GO I BLANK (1A1A2A(19+21) I IA1A3A15	-     ATL521* SƏ1 _
30 37 4	F129.2.NN	ATL301* SƏ1 STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON	
		INDIGATORS I DISPLAY I REPLACE ASSEMBLIES	[
30 38 30 39 30 40		SPARE SPARE SPARE	
30 41 1 30 42	T130	TEST LDCA CONTROL Compare the B register to A0000007 Branch to Major 30 Minor 43 on ND-GO Branch to Major 30 Minor 51	
30 43 2 30 44	T130.N	TEST FOR FAULT IN "SHORT DATA EN" INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH O7BFFF0FFF	NAD->INMX, INMX->BREG ON
		PULSE CA DRIVERS WITH 00000007 Compare the B register to A0000007 Pranch the Major 20 Ningr 47 on Ningro	LOAD EN

TESTIC		I TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
30 45	3	T1 30•NG	TEST FOR NO CLEAR OF AREG LOAD A REGISTER WITH AFFFE INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH O7BFFFOFFF PULSE CP DRIVERS WITH F COMPARE THE B REGISTER TO AFFFE BRANCH TO MAJOR 30 MINOR 46 ON NO-GO	NAD->INMX, INMX->BREG ON LOAD EN
	4	F130.NGG	ITL211* SƏ1 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
			IINDICATOBSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GOIBLANKIIAIA3A24I	
30 46	4	F130.NGN	INPUT TO BRA101 Enable vertical parity check Stop Tape, display C register, NO-GO light on	
			INDICATORS I DISPLAY I REPLACE ASSEMBLIES	
30 47	3	F130.NN	ATA103* SƏ1 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT DN	
			I INDICATORS I DISPLAY I REPLACE ASSEMBLIES	
30 48 30 49 30 50			SPARE SPARE SPARE	
30 51 30 52	1	T131	TEST CL CA => GTA000*->MTW1 SERIALLY LOAD THE B REGISTER WITH AF INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF1FFF0FFF	MTW1->INMX. INMX->BREG ON
			PULSE CA DRIVERS WITH THE A REGISTER COMPARE THE B REGISTER TO A LOGICALLY "AND" C REGISTER AND A8 - RESULT IN B & C REGISTER BRANCH TO MAJOR 30 MINOR 53 ON ND-GO BRANCH TO MAJOR 30 MINOR 59	CLEAR EN
30 53 30 54	2	T131.N	TEST CL CE => GTE000*->MTW1 SERIALLY LOAD THE B REGISTER WITH AF INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF1FFF0FFF	MTW1->INMX, INMX->BREG O CLEAR EN

TESTIDEC		TEST/FAULT	SELF-TEST PROGRAM	1 REMARKS
			PULSE GE DRIVERS WITH THE A REGISTER COMPARE THE B REGISTER TO A Logically 'And' c register and A4 - result in B & c register Branch to major 30 minor 55 on ND-GO	
:	3	F131.NG	FAULT IN GTAOOO*->QUTOO1 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT DN	
			I <u>INDICATORS I DISPLAY I REPLACE ASSEMBLIES</u> INO GO I BLANK IIAIAZA(12,13) I IIAIA4A11	I
055	3	F131.NN	ATL421* SƏ1 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
			INDICATORS         I DI SPLAY         I         REPLACE ASSEMBLIES         I           IND GD         I         40000000011A1A2A(19,21)         I         I           I         I         1         IIIA1A3A15         I	
056 057 058			SPARE SPARE SPARE	
059 060	1	T 1 32	TEST LDCE RESET TST2 Initiate self test mode 2-load self test register with 078FFF4FFF Pulse ce drivers with 00000F8	NAD->INMX, INMX->BREG ON LOAD EN, SIM NO-GO
:	2	F132.1	FAULT LOC WITHIN TEST T132 , NOT A PROGRAMMED STOP- LDCE LATCH NOT RESET	
1	1	T132(CONT)	BRANCH TO MAJOR 30 MINOR 62 ON NO-GO BRANCH TO MAJOR 30 MINOR 66	
0 61			SPARE	
30 62 ;	2	F132.2	LDCE IBT OR LATCH FAULT Enable vertical parity check Stop Tape, display C register, no-go light on	

TESTIDECISION	TEST/FAULT 1NUMBER	I SELF-TEST PROGRAM	REMARKS
		INDICATORSDISPLAY1BEPLACE_ASSEMBLIES NO_GOIBLANKLIAIA2A(10+13+17)	1
30 63 30 64 30 65		SPARE Spare Spare	
30 66 1 30 67	T1 33	TEST LDCE CONTROL Compare the B register to A00000F8 Branch to Major 30 Minor 69 on ND-Go Branch to Major 30 Minor 73	
30 68		SPARE	
30 69 2	F133.N	ATE103# SƏ1 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I <u>INDICATORS I DISPLAY I BEPLACE ASSEMBLIES</u> IND GQ137011A1A2A(9.13)	
30 70 30 71 30 72		SPARE SPARE SPARE	
30 73 1 30 74	T134	TEST CL CE => GTE000*->QUT002(MTW1) INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF1FFF0FFF PULSE CE DRIVERS WITH THE A REGISTER COMPARE THE B REGISTER TO A LOGICALLY 'AND' C REGISTER AND A4 - RESULT IN B & C REGISTER BRANCH TO MAJOR 30 MINOR 76 ON NO-GO BRANCH TO MAJOR 30 MINOR 79	MTW1->INMX, INMX->BREG ON Clear en
30 75		SPARE	
30 76 2	F134.N	FAULT IN GTE000* -> QUT002 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, ND-GD LIGHT ON	

TESTIO		I TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
			I	
30 77 30 78			SPARE SPARE	
30 79 30 80	1	T135	TEST LDCI RESET OF TST2 Initiate Self test mode 2-load self test register with 07BFFF4FFF Pulse CI drivers with 0001F00	NAD->INMX, INMX->BREG ON LOAD EN, SIM NO-GO
	2	F135.1	FAULT LOC WITHIN TEST T135 , NOT A PROGRAMMED STOP- LDCI LATCH NDT RESET	
	1	T135(CONT)	BRANCH TO MAJOR 30 MINOR 82 ON NO-GO BRANCH TO MAJOR 30 MINOR 85	
30 81			SPARE	
30 82	2	F135.2	LDCI IBT OR LATCH FAULT ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GOIRLANKILAIA2A(10+13+16)	
30 83 30 84			SPARE SPARE	
30 85 30 86	1	T1 36	TEST LDCI CONTROL Compare the B register to A0001F Branch to Major 30 minor 88 on ND-Go Branch to Major 30 minor 91	
30 87			SPARE	
30 88	2	F136.N	ATI103* SƏ1 Enable vertical parity check STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	

TESTIDECISIO	DN I TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
		IINDICATORSL_DISPLAYLREPLACE_ASSEMBLIES IND_GDI1740011A1A2A19+131	:{
30 89 30 90		SPARE SPARE	
30 91 1 30 92	T137	TEST CL CI => GT1000*->QUT003(MTW1) INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF1FFF0FFF PULSE CI DRIVERS WITH THE A REGISTER COMPARE THE B REGISTER TO A LOGICALLY 'AND' C REGISTER AND A2 - RESULT IN B & C REGISTER BRANCH TO MAJOR 30 MINOR 94 ON NO-GO BRANCH TO MAJOR 30 MINOR 98	MTW1->INMX, INMX->BREG ON Cléar en
30 93		SPARE	
30942	F137.N	FAULT IN GTI000*->QUT003 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON <u>I INDICATORS I DISPLAY L' REPLACE ASSEMBLIES</u> NO GO I 2000000011A1A2A(12,13) <u>I IA1A4A10</u>	- - - - -
30 95 30 96 30 97		SPARE SPARE SPARE	
30.09		ENADLE VEDTICAL DADITY CUECK	

30 98	ENABLE VERTICAL PARITY CHECK
30 99	END OF MAJOR TEST

	ECISION	I TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
si oo			INITIALIZE DEFINE SELF TEST TAPE ENABLE LOW LEVEL ON GTC001* BRANCH TO MAJOR 31 MINOR 3	
81 01			STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
31 02	2	F31.4 F192.1	CBC335# S@1 OR ABS115 S@0 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
			IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES	
1 03 1 04	1	T138	TEST LDCP RESET OF TST2 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH 07BFFF4FFF	NAD->INMX+ INMX->BREG ON LOAD EN+ SIM NO-GO
	_		PULSE CP DRIVERS WITH FFFE	
	2	F138.1	FAULT LOC WITHIN TEST T138 , NOT A PROGRAMMED STOP- LOCP LATCH NOT RESET	
	I	F138(CONT)	BRANCH TO MAJOR 31 MINOR 6 ON NO-GO Branch to major 31 minor 9	
1 05			SPARE	
1 06	2	F138.2	FAULT IN LDCP IBT OR LATCH ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI	I
1 07 1 08			IND_GDIBLANKIIAIA2A(10+13+17)I SPARE SPARE	
1 09 1 10	1	T139	TEST LDCP CONTROL Compare The 8 register to AFFFE Branch to Major 31 Minor 12 on No-Go Branch to Major 31 Minor 15	
. 11			SPARE	

TESTIDEC	CISION   TEST/FAU EVELNUMBER		I REMARKS
31 12 2	2 F139•N	ATP103* SƏ1 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYI	<u>-</u> 1
31 13 31 14		SPARE SPARE	
31 15 1 31 16	1 T140	TEST CLEAR OF AREG DURING GEN LOAD LOAD A REGISTER WITH AFFFE INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH 078FFF0FFF PULSE CP DRIVERS WITH F COMPARE THE B REGISTER TO AF BRANCH TO MAJOR 31 MINOR 18 ON NO-GO BRANCH TO MAJOR 31 MINOR 21	NAD->INMX, INMX->BREG ON LOAD EN
31 17		SPARE	
31 18 2	2 F140.N	IARO29* SƏ1 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I <u>INDICATORS I DISPLAY I REPLACE ASSEMBLIES</u> INO GO I 77760000 1A1A3A(12,14)	
1 19		SPARE SPARE	
1 21 1 31 22	1 7141	TEST CL CP -> MTW1 => GTP000*->QUT004 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF1FFF0FFF PULSE CP DRIVERS WITH THE A REGISTER COMPARE THE B REGISTER TO A LOGICALLY 'AND' C REGISTER AND A1 - RESULT IN B & C REGISTER BRANCH TO MAJOR 31 MINOR 24 ON NO-GO BRANCH TO MAJOR 31 MINOR 27	MTW1->INMX, INMX->BREG ON CLEAR EN
31 23		SPARE	
31 24	2 F141.N	FAULT IN GTP000*->QUT004 ENABLE VERTICAL PARITY CHECK	

TESTICECISI	ON   TEST/FAULT	SELF-TEST PROGRAM	REMARKS
		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON  IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI INO GO I 10000000011A1A2A(12,13,19) IIIA1A4A10	
31 25 31 26		SPARE SPARE	
81 27 1 81 28	T142	TEST LDCM RESET TST2 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFAFFF4FFF PULSE THE CM DRIVERS WITH FFB	JCM->INMX, INMX->BREG ON LOAD EN, SIM NO-GO
2	F142.1	FAULT LOC WITHIN TEST T142 , NOT A PROGRAMMED STOP- LDCM LATCH NOT RESET	
1	T142(CONT)	BRANCH TO MAJOR 31 MINOR 30 ON NO-GO Branch to major 31 minor 33	
31 29		SPARE	
31302	F142.2	FAULT IN LOCM IBT OR LATCH, OR GATING ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I <u>INDIGATORSI DISPLAYI REPLACE ASSEMBLIES</u> IND.GOI BLANKIIAIA2A(10,12,13,17)	
31 31 31 32		SPARE Spare	
81 33 1 81 34	T143	TEST LDCM CONTROL Compare the B register to AFF8 Branch to Major 31 minor 35 on ND-Go Branch to Major 31 minor 40	
31 35 2	T143.N	TEST FOR CM DR EN SƏO Compare The B register to Aofb Branch to Major 31 minor 36 on No-Go	
3	F143.NG	FAULT IN CM DR EN ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	

TESTICE		TEST/FAULT 1NUMBER	I SELF-TEST PROGRAM	
			IINDICATORSL_DISPLAYLREPLACE_ASSEMBLIES IND_GOL_BLANK11A1A2A07	 _1
1 36	3	¥143.NN	TEST FOR CM DR EN SOO Compare the B register to AF Branch to Major 31 minor 37 on NO-Go	
	4	F143.NNG	FAULT IN CM DR EN ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON	
			I INDICATORS I DISPLAY I REPLACE ASSEMBLIES	 _1 _1
1 37	4	F143.NNN	ATM103* SƏ1 ENABLE VERTICAL PARITY CHECK COMPARE THE B REGISTER TO AFF8 STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON I <u>INDICATORSI_DISPLAYI</u>	- -1 -1
138 139			SPARE SPARE	
1 40 1 41	1	T144	TEST CL CM -> MTW1 => GTM010*->QUT005 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF1FFF0FFF PULSE THE CM DRIVERS WITH THE A REGISTER COMPARE THE B REGISTER TO A LOGICALLY 'AND' C REGISTER AND A08 - RESULT IN B & C REGISTER BRANCH TO MAJOR 31 MINOR 43 ON NO-GO BRANCH TO MAJOR 31 MINOR 46	MTW1->INMX, INMX->BREG O Clear En
31 42			SPARE	
1 43	2	F144.N	FAULT IN GTMO10* -> QUTOO5 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	

	DECISION	I TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
			I INDICATORS I I REPLACE_ASSEMBLIES IND GD I 40000000 1A1A2A(13,15,19) I I 1A1A4A10	
31 44 31 45			SPARE SPARE	
31 46 31 47	1	T145	TEST LDMB RESET OF TST2 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OEBFFF4FFF PULSE THE MB DRIVERS WITH FFFFFFF	WD1->INMX, INMX->BREG ON LOAD EN, SIM NO-GO
	2	F145.1	FAULT LOC WITHIN TEST T145 , NOT A PROGRAMMED STOP- LDMB LATCH NOT RESET	
	1	T145(CONT)	BRANCH TO MAJOR 31 MINOR 49 ON NO-GO BRANCH TO MAJOR 31 MINOR 52	
31 48			SPARE	
31 49	2	F145.2	FAULT IN LOMB IBT OR LATCH, OR IN INST DECODE MATRIX ENABLE VERTICAL PARITY CHECK PUNCH TAPE CODES - /9 /E &C STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON INDIGATORS I DISPLAY I	INVALID INST = 3/5/1 OCTAL
31 50 31 51			SP AR E SP AR E	
31 52 31 53	1	T146	TEST LDMB CONTROL Compare The B register to AFFFFFF Branch to Major 31 minor 55 on ND-Go Branch to Major 31 minor 58	
31 54			SPARE	
31 55	2	F146.N	ATB203* SƏ1 Enable vertical parity check Stop tape, display c register, nd-go light on	

TESTIDECISION	I TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
1 56		IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GDI_17777777711A1A2A14+131I SPARE	
1 57		SPARE	
31 58 1 31 59	T147	TEST CL MB -> MTW1 => GTB000*->QUT006 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF1FFF0FFF	MTW1->INMX, INMX->BREG ON Clear en
		PULSE THE MB DRIVERS WITH THE A REGISTER COMPARE THE B REGISTER TO A LOGICALLY 'AND' C REGISTER AND A04 - RESULT IN B & C REGISTER BRANCH TO MAJOR 31 MINOR 61 ON NO-GO BRANCH TO MAJOR 31 MINOR 64	
1 60		SPARE	
1612	F147.N	FAULT IN GTB000*->QUT006 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I INDICATORS I DISPLAY I REPLACE ASSEMBLIES NO GO I 200000011A1A2A(10,11,13)	
1 62 1 63		SPARE SPARE	
164 1 165	T148	TEST LXMB RESET OF TST2 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBDFF4FFF	XMB->INMX+ INMX->BREG ON LOAD EN, SIM NO-GO
2	51/0 1	PULSE THE XMB DRIVERS WITH FFFFFF	
2	F148.1	FAULT LOC WITHIN TEST T148 , NOT A PROGRAMMED STOP- LOXM LATCH NOT RESET	
1	T148(CONT)	BRANCH TO MAJOR 31 MINOR 67 ON ND-GD Branch to Major 31 minor 70	
1 66		SPARE	
1 67 2	F148.2	FAULT IN LXMB IBT OR LATCH	

ITESTIC		TEST/FAULT	SELF-TEST PROGRAM	REMARKS
			ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
			IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES NO_GOIBLANKIIAIA2A(10+13+17)	
31 68 31 69			SPARE SPARE	
31 70 31 71	1	T149	TEST LXMB CONTROL COMPARE THE B REGISTER TO AFFFFFF BRANCH TO MAJOR 31 MINOR 73 ON NO-GO BRANCH TO MAJOR 31 MINOR 76	
31 72			SPARE	
31 73	2	F149.N	ATX103# SƏ1 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I	
31 74 31 75			SPARE SPARE	
31 76 31 77	1	T 1 50	TEST LXMB => CL MB -> MTW1 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF1FFF0FFF	MTW1->INMX, INMX->BREG ON
			PULSE THE XMB DRIVERS WITH THE A REGISTER Compare the B register to A Logically "And" C register and AO4 - result in B & C register Branch to Major 31 minor 79 on ND-Go Branch to Major 31 minor 82	CLEAR EN
31 78			SPARE	
31 79	2	F150.N	ATX102* SƏ1 Enable vertical parity check STOP TAPE, display c register, no-go light on	

TESTIC		I TEST/FAULT	I SELF-TEST PROGRAM	REMARKS
			III REPLACE_ASSEMBLIESI	
31 80 31 81			SP AR E SP AR E	
31 82 31 83	1	T151	TEST LDW1 RESET OF TST2 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH 078FFF4FFF	NAD->INMX, INMX->BREG ON Load en, SIM ND-GO
			PULSE THE WORD 1 DRIVERS WITH FFFFFFF	
	2	F151.1	FAULT LOC WITHIN TEST T151 , NOT A PROGRAMMED STOP- LDW1 LATCH NOT RESET	
			I INDIGATORS I DISPLAY I REPLACE, ASSEMBLIES	
	1	T151(CONT)	BRANCH TO MAJOR 31 MINOR 85 ON NO-GO Branch to Major 31 minor 87	
31 84			SPARE	
31 85	2	F151.2	FAULT IN LOWI IBT OR LATCH, OR INST DECODE MATRIX ENABLE VERTICAL PARITY CHECK PUNCH TAPE CODES - /0 /E &C STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I INDICATORS	INVALID INST = OCTAL 3/4/0
31 86			SPARE	
31 87 31 88	1	T152	TEST LDW1 CONTROL Compare the B register to AFFFFFF Branch to Major 31 Minor 90 on NO-Go Branch to Major 31 Minor 92	
31 89			SPARE	
31 90	2	F152.N	ATW103* SƏ1 Enable vertical parity check Stop tape, display C register, NÖ~GO light on	

TESTIDECISION	TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
		IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES	
31 91		SPARE	
31 92 1 31 93	т153	TEST CL WD1 -> MTW1 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF1FFFOFFF PULSE THE WORD 1 DRIVERS WITH THE A REGISTER COMPARE THE B REGISTER TO A LOGICALLY 'AND' C REGISTER AND AF - RESULT IN B & C REGISTER BRANCH TO MAJOR 31 MINOR 95 ON NO-GO BRANCH TO MAJOR 31 MINOR 98	MTW1->INMX, [NMX->BREG ON CLEAR EN
31 94		SPARE	
31 95 2	F153.N	FAULT IN CL WD1 EN OF CFLG DR         ENABLE VERTICAL PARITY CHECK         STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON         I	ATW102* SƏ1 ITW151* SƏ1 INPUT TO ATA100 SƏ1 INPUT TO ATE100 SƏ1 INPUT TO ATE100 SƏ1 INPUT TO CTP100 SƏ1
31 96 31 97		SPARE SPARE	

31 98ENABLE VERTICAL PARITY CHECK31 99END OF MAJOR TEST

ITESTICECISION   TEST/FAULT	SELF-TEST PROGRAM	REMARKS I
32 00 32 01 32 02	BRANCH TO MAJOR 32 MINOR 3 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
32 03 1 T154	TEST INPUT TO MBCO61 FOR Sal Branch to Major 33 minor 1	
32 04	END OF MAJOR TEST	

ITESTIDECISION   TEST/F		I REMARKS I
33 00 2 F30.6	FAULT IN 6SB OF MABC	
	INDICATORS I DISPLAY I REPLACE ASSEMBLIES	1
	PUNCH TAPE LEACER 12 INCHES LONG Branch to major 33 minor 3	
33 01	BRANCH TO MAJOR 33 MINOR 3	
33 02 2 F30.7	FAULT IN 658 OF MABC Stop tape, display c register, no-go light on	
	INDICATORS I DISPLAY I REPLACE ASSEMBLIES	}
33 03	END OF MAJOR TEST	

TESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS I
34 00 34 01 34 02	BRANCH TO MAJOR 34 MINOR 3 Stop Tape, display C register, NO-go light on Stop Tape, display C register, NO-go light on	

-			•		
34	03	END	OF	MAJOR	TEST

TESTIDECISION	I TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
1	************* * *	COMPUTER MONITOR CONTROL TESTS- TEST OF ALL"READ AND COMPARE"FUNCTIONS	***************************************
1	• • •	MAJORS 35, 36, AND 37	* * *
•		***************************************	*****
35 00		INITIALIZE DEFINE SELF TEST TAPE SET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST NCU CLOCK MODE (GTC003*) ENABLE LOW LEVEL ON GTC001* BRANCH TO MAJOR 35 MINOR 3	
35 01 35 02		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
35 03 1	T155	TEST RCAA, NO ITERATION	
35 04		PREVIOUS TEST * (32)T154 SERIALLY LOAD THE B REGISTER WITH A INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH 8FBFFF0FFF READ & COMPARE THE NAD LINES WITH AFFFFFFF; PULSE XT0101	ROM->WD1 DR
2	F155.1	FAULT LOC WITHIN TEST T155, NOT A PROGRAMMED STOP- IN PROCESS FAULT Detected	
		INDICATORS         DISPLAY         REPLACE ASSEMBLIES         I           ITEST SET FAULT I         100000011A1A4A15         I           ITEST SET FAULT I         12A1A1A(1.14.17)         I           ITEST SET FAULT I         200012A1A1A02         I	
1	T155(CONT)	BRANCH TO MAJOR 35 MINOR 5 ON NO-GO Branch to Major 35 minor 11	
35 05 2 35 06	T155.2	TEST RCXM TO ISOLATE EN FAULT SERIALLY LOAD THE 8 REGISTER WITH A INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH 1FBFFFOFFF READ & COMPARE THE XMB LINES WITH AFFFFFFF BRANCH TO MAJOR 35 MINOR 7 ON NO-GO	ROM->XM8 DR
3	F155.2.G	AAC212* SƏ1 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	

ITESTIDECISIO	IN   TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS I
		I INDICATORS I DISPLAY I REPLACE ASSEMBLIES	
35 07 3	F155.2.N	"NCU->STE 8.T.*" INACTIVE ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON INDICATORSI.DISPLAY L	AAR065* SƏ1
35 08 35 09 35 10		SPARE SPARE SPARE	
35 11 1 35 12	T156	TEST RESULT OF RCAA Compare the B register to Affffff Branch to Major 35 minor 13 on No-Go Branch to Major 35 minor 21	
35 13 2 35 14	T156.N	TEST R&C GATING WITH RCXM SERIALLY LOAD THE B REGISTER WITH A INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH 1FBFFF0FFF READ & COMPARE THE XMB LINES WITH AFFFFFFF COMPARE THE B REGISTER TO AFFFFFFF BRANCH TO MAJOR 35 MINOR 17 ON NO-GO	ROM->XMB DR
35 15 3	T156.NG	TEST R&C GATING FURTHER WITH RCW1 SERIALLY LOAD THE B REGISTER WITH A INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH 8F8FFF0FFF READ & COMPARE WORD 1 WITH AFFFFFFF COMPARE THE B REGISTER TO THE A REGISTER BRANCH TO MAJOR 35 MINOR 16 ON NO-GO	ROM->WD1 DR
4	F156.NGG	FAULT IN RCAA IBT OR LATCH, OR INST DECODE MATRIX ENABLE VERTICAL PARITY CHECK PUNCH TAPE CODES - /6 /F &C STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	

TESTIDECISION	TEST/FAULT	I SELF-TEST PROGRAM	REMARKS
		IINDICATORSI_DISPLAY IREPLACE_ASSEMBLIES I TEST SET FAULT   40000000 1A1A2A17 II NO_GOI_BLANKIPROCEED_PER_PARAGRAPH_3=12D	INST DECODE MATRIX
5164	F156.NGN	FAULT IN LCU R&C GATING ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I <u>INDICATORS I DISPLAY I REPLACE ASSEMBLIES</u> IND_GOII777777711A1A4A116.191	IAC112* 501
95 17 3 15 18	T156.NN	ISOLATE R&C FAULT BETWEEN LCU & SCU SERIALLY LOAD THE B REGISTER WITH A READ & COMPARE PJB LINES WITH AFFFFFF COMPARE THE B REGISTER TO THE A REGISTER BRANCH TO MAJOR 35 MINOR 19 ON NO-GO	
4	F156,NNG	FAULT IN LCU->SCU REC GATING ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSDISPLAY	IAC330* SƏ1
35 19 4	F156,NNN	FAULT IN SCU R&C GATING ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES IND_GOI_1777777712A1A1A(1,2)	[AR025* S@1
5 20		SP AR E	
95 21 1 95 22	Ŧ157	TEST "DISPLAY AA" => XTD101->QUM041 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBEFFOFFF READ & COMPARE THE NAD LINES WITH A0000008; PULSE XTD101 LOGICALLY 'AND' C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS BRANCH TO MAJOR 35 MINOR 24 ON NO-GO BRANCH TO MAJOR 35 MINOR 26	EXMW->INMX
5 23		SPARE	

	ECISION	I TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
35 24	2	F157.N	FAULT IN EN "DISPLAY AA" STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
			IINDICAIDRSI_DISPLAY_IBEPLACE_ASSEMBLIESI INO_GOI10:1A1A4A(16:19)I	
35 25			SPARE	
35 26 35 27	1	T158	TEST RCAA, WITH ITERATION SERIALLY LOAD THE B REGISTER WITH AFFFFFFF INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH 8FBFFF07FF READ & COMPARE THE NAD LINES WITH A; PULSE XTD101	BREG->ROM, ROM->WD1 DR Should result in ND-GD, CREG=OFFFFFF
	2	F158.1	FAULT LOC WITHIN TEST T158, NOT A PROGRAMMED STOP- IN PROCESS FAULT DETECTED IINDICATORSI_DISPLAYI	
	1	T158(CONT)	BRANCH TO MAJOR 35 MINOR 31 ON NO-GO BRANCH TO MAJOR 35 MINOR 29	
35 28			SPARE	
35 29	2	F158.2	FAULT IN ITERATION CONTROL ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSL DISPLAYREPLACE_ASSEMBLIESI IND_GOIBLANKIZAIAIA(13:14:17)I	
35 30			SPARE	
35 31 35 32	1	T159	TEST RCAM, COMPARE => NO-GO SERIALLY LOAD THE B REGISTER WITH AFFFFFFF INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH BFBFFF07FF READ & COMPARE THE NAD LINES WITH A; PULSE XTD102	BREG->ROM, ROM->WD1 DR
	2	F159.1	FAULT LOC WITHIN TEST 159, NOT A PROGRAMMED STOP- RCAM LATCH NOT RESET	

	ECISION	I TEST/FAULT	I SELF-TEST PROGRAM	REMARKS
	1	T159(CONT)	I INDIGATORS I DISPLAY I BEPLACE ASSEMBLIES ITEST SET FAULT I 100000011A1A4A15 BRANCH TO MAJOR 35 MINOR 38 ON NO-GO BRANCH TO MAJOR 35 MINOR 34	
35 33			SPARE	
35 34	2	F159.2	FAULT IN RCAM IBT, LATCH, ETC ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I <u>INDICATORS I DISPLAY I</u> <u>REPLACE ASSEMBLIES</u>	
35 35 35 36 35 37			SPARE SPARE SPARE	
35 38 35 39	1	т160	TEST "DISPLAY AM" => XTD102->QUM045 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBEFFOFFF READ & COMPAKE THE NAD LINES WITH A000008; PULSE XTD102 LOGICALLY 'AND' C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS BRANCH TO MAJOR 35 MINOR 41 ON NO-GO BRANCH TO MAJOR 35 MINOR 43	EXMW->INMX
35 40			SPARE	
35 41	2	F160.N	FAULT IN EN "DISPLAY AM" ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
			IINDICATORSI_DISPLAY_IREPLACE_ASSEMBLIES NO_GOI200]1A1A4A116.191	
35 42			SPARE	
35 43 35 44	1	T161	TEST RCAQ, COMPARE => NO-GO SERIALLY LOAD THE B REGISTER WITH AFFFFFFF INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH 8FBFFF07FF READ & COMPARE THE NAD LINES WITH A; PULSE XTD103	BREG->ROM, ROM->WD1 DR

	ECISION	I TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
	2	F161.1	FAULT LOC WITHIN TEST 161, NOT A PROGRAMMED STOP- RCAQ LATCH NOT RESET	
	1	T161(CONT)	BRANCH TO MAJOR 35 MINOR 51 ON NO-GO BRANCH TO MAJOR 35 MINOR 46	
5 45			SPARE	
5 46	2	F161.2	FAULT IN RCAQ IBT, LATCH, ETC Enable vertical parity check stop tape, display c register, no-go light on	
			I INDICATORS I DISPLAY I REPLACE ASSEMBLIES NO GO I BLANK (1A1A2A18 I ILA1A4A(15.16)	
5 47 5 48 5 49 5 50			SPARE SPARE SPARE SPARE	
5 51 5 52	1	τ162	TEST "DISPLAY AQ" => XTD103->QUM044 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBEFFOFFF READ & COMPARE THE NAD LINES WITH A000004; PULSE XTD103 LOGICALLY 'AND' C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS BRANCH TO MAJOR 35 MINOR 54 ON NO-GO BRANCH TO MAJOR 35 MINOR 56	EXMW->INMX
553			SP AR E	
5 54	2	F162.N	FAULT IN EN "DISPLAY AQ" ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I INDICATORS I DISPLAY L REPLACE ASSEMBLIES INO GO	ł
5 55			SPARE	
5 56 5 57	1	T163	TEST RCMB, COMPARE => NO-GO Serially load the B register with Afffffff Initiate Self test mode 2~load self test register with 8f8fff07ff	BREG->ROM, ROM->WD1 DR

		TEST/FAULT 1NUMBER	I SELF-TEST PROGRAM	REMARKS
	2	F163.1	FAULT LOC WITHIN TEST 163, NOT A PROGRAMMED STOP- RCMB LATCH NOT RESET	
			INDICATORS I DISPLAY I REPLACE ASSEMBLIES	
	1	T163(CONT)	READ & COMPARE THE NAD LINES WITH A: PULSE XTD104* Branch to Major 35 minor 64 on NO-Go Branch to Major 35 minor 59	
5 58			SPARE	
5 59	2	F163.2	FAULT IN RCMB IBT, LATCH, ETC ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
			INDICATORS I DISPLAY I REPLACE ASSEMBLIES I NO GO I BLANK [1A1A2A18   I IA1A4A(15.16)	
5 60			SPARE	
5 61 5 62 5 63			SPARE SPARE SPARE	
5 64 5 65	1	T164	TEST "DISPLAY MB" => XTD104*->QUM047 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBEFFOFFF READ & COMPARE THE NAD LINES WITH A; PULSE XTD104* LOGICALLY 'AND' C REGISTER AND A00002 - RESULT IN B & C REGISTER BRANCH TO MAJOR 35 MINOR 67 ON NO-GO BRANCH TO MAJOR 35 MINOR 71	EXMW->INMX
5 66			SPARE	
5 67	2	F164.N	FAULT IN EN "DISPLAY MB" ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
			IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIESI INO_GOI100011A1A4A(16+19)I	
5 68			SPARE	

		I TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS I
35 71 35 72	1	T165	TEST RCCA, COMPARE => NO-GO SERIALLY LOAD THE B REGISTER WITH AFFFFFFF INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH 2FBFFF07FF READ & COMPARE THE CA LINES WITH A	BREG->ROM, ROM->MB
	2	F165.1	FAULT LOC WITHIN TEST 165, NOT A PROGRAMMED STOP- RCCA LATCH NOT RESET	1
	1	T165(CONT)	BRANCH TO MAJOR 35 MINOR 84 ON NO-GO	
35 73	2	T165.2	TEST FOR READ CA EN FAULT Compare the B register to A Branch to Major 35 minor 75 on NO-GO	
35 74	3	F165.2.G	READ CA FAULT ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON I	   AACO22* SƏ1
			IND_60IBLANKIIA1846(15+16)	1 AALU22+ SØI
35 75 35 76	3	T165.2.N	TEST LOAD OF BREG Compare the 8 register to AFFFFFF Branch to major 35 minor 80 on NO-GO	
35 77	4	T165.2.NG	TEST R&C GATING READ & COMPARE THE MA LINES WITH A007FFF ~ Compare the B register to the A register Branch to Major 35 minor 78 on ND-GO	
	5	F165.2.NGG	FAULT RCCA IBT, LATCH Enable vertical parity check Stop tape, display c register, NO-GO light on	
			I INDICATORS I DISPLAY IBEPLAGE ASSEMBLIES NO GO   BLANK  1A1A2A18  IL6184A(15.16)	1
35 <b>78</b>	5	F165.2.NGN	FAULT IN REC GATING ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	

TESTIDECISIO	N   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
		I INDICATORS I DISPLAY I REPLACE ASSEMBLIES   INO GO I 177776011A1A4A(16.19)	
35 79		SPARE	
35804	F165.2.NN	NOT A NORMAL FAULT LOCATION ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSIDISPLAYREPLACE_ASSEMBLIESI INO_GOIXXXXXXXXIPROCEED_PER_PARAGRAPH_3-13I	
35 81 35 82 35 83		SPARE Spare Spare	
35 84 1 35 85	T166	TEST RCCE, COMPARE => NO-GO SERIALLY LOAD THE B REGISTER WITH AFFFFFF INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH 2FBFFF07FF READ & COMPARE THE CE LINES WITH A	BREG->RDM, ROM->MB
2	F166.1	FAULT LOC WITHIN TEST 166, NOT A PROGRAMMED STOP- RCCE LATCH NOT RESET	
1	T166(CONT)	BRANCH TO MAJOR 35 MINOR 90 ON ND-GO	
35 86 2	T166.2	TEST FOR READ CE EN FAULT Compare the B register to A Branch to Major 35 minor 88 on ND-GO	
35873	F166.2.G	READ CE FAULT ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYI	
35 88 3	F166.2.N	FAULT IN RCCE 18T OR LATCH ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	ARUU177 301

NO_1_LE	SION   TEST/FAULT VEL 1 NUMBER	SELF-TEST PROGRAM	REMARKS
		I INDICATORS I DISPLAY IREPLACE_ASSEMBLIES^ NO GO I 17777777711A1A2A18 IIA1A4A(15,16)	-से   
5 89		SPARE	
5901 591	T167	TEST RCCI, COMPARE => NO-GO Serially Load the B register with Affffff Initiate self test mode 2-load self test register with 2fbfff07ff Read & Compare the CI lines with A	BREG->ROM+ ROM->MB
2	F167.1	FAULT LOC WITHIN TEST 167, NOT A PROGRAMMED STOP- RCCI LATCH NOT RESET	1
1	T167(CONT)	BRANCH TO MAJOR 35 MINOR 98 ON NO-GO	
5922	T167.2	TEST FOR READ CI EN FAULT Compare the B register to a Branch to Major 35 minor 94 on ND-GO	
i 93 3	F167.2.G	READ CI FAULT ENABLE VERTICAL PARITY CHECK Stop Tape, Display C register, NO-GO Light On	
		I <u>INDICATORS I DISPLAY I REPLACE ASSEMBLIES</u> INO GO I BLANK ILALA4AI15,171	AACO21* SƏ1
5943	F167.2.N	FAULT IN RCCI IBT OR LATCH Enable vertical parity check Stop Tape, display c register, nd-go light on	
		1	   
5 95		SPARE SPARE	

TESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS I
35 98 35 99	ENABLE VERTICAL PARITY CHECK END OF MAJOR TEST	

TESTICECISION	I TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
5002	F30.8	FAULT IN LSB OF MABC	
		PUNCH TAPE LEADER 12 INCHES LONG	
		INITIALIZE DEFINE SELF TEST TAPE SET INNIBIT INCREMENT CP FLAG & ENABLE SELF TEST NCU CLOCK MODE (GTC003+) ENABLE LOW LEVEL ON GTC001* BRANCH TO MAJOR 36 MINOR 3	
6 01		STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON	
36 02 2	F30.9	FAULT IN LSB OF MABC STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I INDICATORS I DISPLAY I REPLACE ASSEMBLIES	
6031 604	T168	TEST RCCP, COMPARE => NO-GO Serially Load the B register with AFFFE Initiate self test node 2-load self test register with 2FBFFF07FF Read & Compare the CP lines with A	BREG->ROM, ROM->MB
2	F168.1	FAULT LOC WITHIN TEST 168, NOT A PROGRAMMED STOP- RCCP LATCH NOT RESET	
1	T168(CONT)	BRANCH TO MAJOR 36 MINOR 8 ON NO-GO	
6052	T168.2	TEST FOR READ CP EN FAULT Compare the B register to A Branch to Major 36 Minor 7 on ND-Go	
36 06 3	F168.2.G	READ CP FAULT Enable vertical parity check Stop Tape, display c register, no-go light on	

	ION   TEST/FAULT	SELF-TEST PROGRAM	REMARKS
		I INDICATORS I DISPLAY I REPLACE ASSEMBLIES	   1AE226* Səl
6073	F168.2.N	FAULT IN RCCP IBT OR LATCH ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		I <u>INDICATORS I DISPLAY I REPLACE ASSEMBLIES</u> IND GO I 17776000011A1A2A18 IIA1A4A(15,16)	1 1 1
6081 609	T169	TEST FOR FAULT IN PART OF EN CP Compare The 8 register to Affe Branch to Major 36 minor 10 on No-Go Branch to Major 36 minor 13	
6 10 2	F169•N	FAULT IN PART OF EN CP ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICAIORSI_DISPLAYI	1
		ING_GOIXXXXXX0000I1A1A4A17	1
36 11 36 12		SPARE SPARE	
36 13 1 36 14	T1 70	TEST RCCM+ COMPARE ≈> ND-GO SERIALLY LOAD THE B REGISTER WITH AFF8 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH 4FBFFF07FF READ & COMPARE THE CM LINES WITH A	BREG->ROM+ ROM->CM DR
2	F170.1	FAULT LOC WITHIN TEST 170, NOT A PROGRAMMED STOP- RCCM LATCH NOT RESET	1
1	T170(CONT)	BRANCH TO MAJOR 36 MINOR 18 ON NO-GO	
6152	T170.2	TEST FOR READ CM EN FAULT COMPARE THE B REGISTER TO A BRANCH TO MAJOR 36 MINOR 17 ON NO-GO	
6163	F170.2.G	READ CM FAULT Enable vertical parity check Stop Tape, display c register, no-go light on	

		I TEST/FAULT	I SELF-TEST PROGRAM	R EMARK S
			IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GOIBLANKIIA1A4AII5+171I	AACO18* SƏl
36 17	3	F170.2.N	FAULT IN RCCM IBT OR LATCH ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON I	
			ING GO I 177600000011A1A2A18 IIAAAA(15.16)	
36 18 36 19	1	T171	TEST RCEA, COMPARE ≠> NO-GO Serially load the B register with AFFFC Load discret input word (Eip/Eup Code) with AFFE00 Read & Compare the EA Lines with A	
	2	F171.1	FAULT LOC WITHIN TEST 171, NOT A PROGRAMMED STOP- RCEA LATCH NOT RESET	
	1	T171(CONT)	BRANCH TO MAJOR 36 MINOR 30 ON NO-GO	
36 20	2	<b>T171.</b> 2	TEST FOR FAULT IN READ EA EN Compare the B register to A Branch to Major 36 minor 22 on NO-GO	
36 21	3	F171.2.G	READ EA FAULT ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYI	AAC026* SƏ1
36 22 36 23	3	T171.2.N	TEST FOR NO LOAD OF BREG Compare the B register to AFFFFC Branch to Major 36 Minor 26 on NO-GO	
36 24	4	T171.2.NG	TEST R&C GATING Read & Compare the EB lines with Affffff Branch to Major 36 Minor 25 on NO-GO	
	5	F171.2.NGG	FAULT IN R&C GATING Enable vertical parity check Stop Tape, display c register, NO-GO light on	

TESTICECISI	ON   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
		I DISPLAY I REPLACE ASSEMBLIES	}
6255	F171.2.NGN	FAULT IN RCEA IBT OR LATCH Enable vertical parity check Stop tape, display c register, ND-GO Light on	
		I INDICATORS I DISPLAY I BEPLACE ASSEMBLIES NO GO (XXXXXXXXXXIA1A2A18 I 1A1A4A18	
6264	F171.2.NN	NOT A NORMAL FAULT LOCATION ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSISPLAYREPLACE ASSEMBLIES IND_GDIXXXXXXXXXIPROCEED PER_PARAGRAPH_3-13	
6 27 6 28 6 29		SPARE SPARE SPARE	
6301 631	T1 72	TEST RCEB, COMPARE => NO-GO SERIALLY LOAD THE B REGISTER WITH AFFFFFFF INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH 2FBFFF07FF READ & COMPARE THE EB LINES WITH A	BREG->ROM, ROM->MB
2	F172.1	FAULT LOC WITHIN TEST 172, NOT A PROGRAMMED STOP- RCEB LATCH NOT RESET	1
1	T172(CONT)	BRANCH TO MAJOR 36 MINOR 38 ON NO-GO	
6322	T172.2	TEST FOR FAULT IN READ EB EN Compare the B register to a Branch to Major 36 minor 34 on No-Go	
6333	F172.2.G	READ E8 FAULT Enable vertical parity check Stop tape, display c register, no-go light on	

TESTIDECISION		SELF-TEST PROGRAM	R EM ARK S
		IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GOI_BLANKIIAIA4A(19.20)	AACOO1* Sal
6343	F172.2.N	FAULT IN RCEB IBT OR LATCH Enable vertical parity check Stop Tape, display c register, nd-go light on	
		I <u>INDICATORS</u> I <u>DISPLAY</u> I <u>BEPLACE ASSEMBLIES</u> I INO GO I 1777777711A1A2A18 I I I I I I I I I I I I I I I I I I I	
86 35 86 36 86 37		SPARE SPARE SPARE	
16 38 1 16 39	¥173	TEST RCFM+ COMPARE => NO-GO SERIALLY LOAD THE B REGISTER WITH AFFFFFFF READ & COMPARE THE FMB LINES WITH A	
2	F173.1	FAULT LOC WITHIN TEST 173, NOT A PROGRAMMED STOP- RCFM LATCH NOT RESET	
1	T173(CONT)	BRANCH TO MAJOR 36 MINOR 45 ON NO-GO	
36402	T173.2	TEST FOR FAULT IN READ FMB EN Compare the B register to A Branch to Major 36 minor 42 on NO-GO	
36413	F173.2.G	READ FMB FAULT ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I	
36 42 3	F173.2.N	IND_GDIBLANKI]A]A4A20I Fault in RCFM ibt or Latch Enable vertical parity check	AAC036* SƏ1

TESTID		TEST/FAULT	I SELF~TEST PROGRAM	REMARKS
			I <u>INDICATORS I DISPLAY I</u> <u>BEPLACE ASSEMBLIES</u> NO GO I 1777777711A1A2A18 I <u>IIIIIIIIIIIIIIIIIIIIIIIIIIIIIIIIIII</u>	
36 43 36 44			SPARE SPARE	
36 45 36 46	1	T174	TEST FOR FAULT IN PART OF READ FMB EN Compare the B register to Affffff Branch to Major 36 Minor 47 on NO-go Branch to Major 36 Minor 51	
36 47	2	F174.N	PART OF READ FMB EN INACTIVE ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I INDIGATORS I DISPLAY I BEPLACE ASSEMBLIES I IND.GO I 1777777711A1A4420	
36 48 36 49 36 50			SPARE SPARE SPARE	
36 51 36 52	1	T175	TEST RCMA, COMPARE => NO-GO Serially load the B register with Afffffff Read & Compare the Ma lines with A	
	2	F175.1	FAULT LOC WITHIN TEST 175, NOT A PROGRAMMED STOP- RCMA LATCH NOT RESET	
	1	T175(CONT)	BRANCH TO MAJOR 36 MINOR 58 ON NO-GO	
36 53	2	T175.2	TEST FOR FAULT IN READ MA EN Compare the B register to A Branch to Major 36 minor 55 on ND-Go	
36 54	3	F175.2.G	READ MA FAULT Enable vertical parity check Stop tape, display c register, nd-go light on	

	ECISION LEVEL	TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
			I INDICATORS I DI SPLAY I REPLACE ASSEMBLIES	   AACO17* SƏ1
6 55	3	F175.2.F	FAULT IN RCMA IBT OR LATCH ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
			Indicators         DISPLAY         BEPLACE ASSEMBLIES           IND GO         I 17777777711A1A2A18           Image: Indicators         I 12777777711A1A2A18	
656 657			SPARE SPARE	
658 659	1	T176	TEST FOR FAULT IN PART OF READ MA EN Compare the B register to A007FFF Branch to Major 36 Minor 60 on ND-go Branch to Major 36 Minor 64	
6 60	2	F176.N	FAULT IN PART OF READ MA Enable vertical parity check Stop tape, display c register, ND-GO light on	
			I INDICATORS I DISPLAY I BEPLACE ASSEMBLIES	1
6 61 6 62 6 63			SPARE SPARE SPARE	
6 64 6 f	1	¥177	TEST RCXM, COMPARE => NO-GO SERIALLY LOAD THE B REGISTER WITH AFFFFFFF INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH 1FBFFF07FF READ & COMPARE THE XMB LINES WITH A	BREG->ROM, ROM->XMB DR
		F177.1	FAULT LOC WITHIN TEST 177, NOT A PROGRAMMED STOP- ROXM LATCH NOT RESET	
			INDICATORS I DISPLAY I REPLACE ASSEMBLIES	1
	1	T1 77 (CONT)	BRANCH TO MAJOR 36 MINOR 72 ON NO-GD	
6 66	2	T177.2	TEST FOR READ XMB EN FAULT Compare the B register to a Branch to Major 36 minor 68 dn nd-go	

	ECISION LEVEL	TEST/FAULT	SELF-TEST PROGRAM	REMARKS
36 67	3	F177.2.G	READ XMB FAULT ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I	AAC103* S@1
36 68	3	F177.2.N	FAULT IN RCXM IBT OR LATCH ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
			NDICATORSDISPLAY1REPLACE_ASSEMBLIES  NO GO   17777777711A1A2A18  1_1A1A4A18	
36 69 36 70 36 71 36 72 36 73	1	T178	TEST RCW1, COMPARE => ND-GO Serially Load the B register with Affffff Initiate self test mode 2-load self test register with 2f8fff07ff Read & Compare word 1 with A	BREG->ROM+ ROM->MB
	2	F178.1	FAULT LOC WITHIN TEST 178, NOT A PROGRAMMED STOP- RCW1 LATCH NOT RESET	
	1	T178(CONT)	BRANCH TO MAJOR 36 MINOR 79 ON NO-GO	
36 74	2	<b>T178.2</b>	TEST FOR READ WI EN FAULT Compare the B register to A Branch to Major 36 Minor 76 on No-Go	
36 75	3	F178.2.G	READ WI FAULT ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I INDIGATORS I DISPLAY I REPLACE ASSEMBLIES IND. GO. I BLANK I JAJA4AJ5	   AAE035* Sə1
36 76	3	F178.2.N	FAULT IN RCW1 IBT OR LATCH, OR INST DECODE MATRIX Enable vertical parity check punch tape codes - /e /d &c stop tape, display c register, no-go light on	INVALID INST = OCTAL 336

	ECISION	I TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
			INDICATORS         DISPLAY         REPLACE ASSEMBLIES           ITEST SET FAULT         4000000011A1A2A16         1           I         11A1A4A(15.16)         1           IND.GO         I.177777771PROGEED_PER_PABAGRAPH_3=12D         1	INST DECODE MATRIX
77 78			SPARE SPARE	
679 680	1	T179	TEST FOR FAULT IN PART OF READ W1 Compare the B register to Affffff Branch to Major 36 Minor 81 on No-Go Branch to Major 36 Minor 86	
6 81	2	F179.N	FAULT IN PART OF READ WI ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON         INDICATORS       I DISPLAY         IND_GO       1         NO_GO       1         17101A164016         IND_GO       1         100.00       1         100.00       1         100.00       1         100.00       1         100.00       1         100.00       1         100.00       1         100.00       1         100.00       1         100.00       1         100.00       1         100.00       1         100.00       1         100.00       1         100.00       1         100.00       1         100.00       1         100.00       1         100.00       1         100.00       1         100.00       1         100.00       1         100.00       1         100.00       1         100.00       1         100.00       1         100.00       1         100.00       1 </td <td></td>	
682 683 684 685			SPARE SPARE SPARE SPARE	
6 86 6 87	1	T180	TEST RCW2, COMPARE => NO-GO Serially Load the B register with Affffff Initiate self test mode 2-load self test register with 4f8fff07ff Read & Compare word 2 with A	BREG->ROM, ROM->CM DR
	2	F180.1	FAULT LOC WITHIN TEST 180, NOT A PROGRAMMED STOP- RCW2 LATCH NOT RESET	}
	1	T1 80 (CONT)	BRANCH TO MAJOR 36 MINOR 93 ON NO-GO	
6 68	2.	T180.2	TEST FOR FAULT IN READ WI EN Compare the B register to A Branch to Major 36 minor 90 on NO-Go	

TESTIDECISION	TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
6893	F180.2.G	READ W2 FAULT ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GOBLANKLIAIA4A15I	AAE036* SƏ1
6903	F180.2.N	FAULT IN RCW2 IBT OR LATCH         ENABLE VERTICAL PARITY CHECK         STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON         Implicators       I display         Indicators       I display         Ind GO       I XXXXXXXXI 1A1A2A14         Implicators       I a1A446(15,16)	
6 91 6 92		SPARE SPARE	
6931 694	T181	TEST FOR FAULT IN PART OF READ W2 Compare the B register to Afffff Branch to Major 36 Minor 95 on NO-GO Branch to Major 36 Minor 98	
6952	F181.N	FAULT IN PART OF READ W2 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIESI NO_GOI_XXXXXXXX0IIAIA4AI7I	
696 697		SPARE SPARE	
6 98 6 99		ENABLE VERTICAL PARITY CHECK End of Major Test	

	LEVEL	I TEST/FAULT	I SELF-TEST PROGRAM	REMARKS
37 00	2	F192.2	FAULT IN 5SB OR BBC738* INPUT TO MBC061	
			I INDICATORS I DISPLAY I REPLACE ASSEMBLIES	
			PUNCH TAPE LEADER 12 INCHES LONG	
			INITIALIZE DEFINE SELF TEST TAPE SET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST NCU CLOCK MODE (GTC003*) ENABLE LOW LEVEL ON GTC001* BRANCH TO MAJOR 37 MINOR 3	
01 01			STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
7 02	1	<b>T3</b> 1	TEST OF TAPE SEARCH TO ADDR < PRESENT ADDR PREVIOUS TEST = (02)T30 BRANCH TO MAJOR 21 MINOR 2	
87 03 87 04	1	T182	TEST RCW3, COMPARE => ND-GO Serially Load The B register with Aff Read & Compare word 3 with A	
	2	F182.1	FAULT LOC WITHIN TEST 182, NOT A PROGRAMMED STOP- RCW3 LATCH NOT RESET	
	1	T182(CONT)	BRANCH TO MAJOR 37 MINOR 11 ON NO-GO	
37 05	2	T182.2	TEST FOR FAULT IN READ W3 EN Compare the B register to a Branch to Major 37 Minor 7 on NO-GO	
37 06	3	F182.2.G	READ W3 FAULT Enable vertical parity check Stop Tape, Display C register, ND-GO light on	

TESTIDECISION	TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
		I_INDICATORS I DISPLAY I	AAE038* SƏ1
37 07 3	F182.2.N	FAULT IN RCW3 IBT OR LATCH Enable vertical parity check Stop Tape, display c register, NO-gd light on	
		I INDICATORS I DISPLAY I REPLACE ASSEMBLIES	
37 08 37 09 37 10		SPARE SPARE SPARE	
37 11 1 37 12	T1 83	TEST FOR FAULT IN PART OF READ W3 Compare the B register to AFF Branch to Major 37 minor 13 on NO-Go Branch to Major 37 minor 18	
37 13 2	F183.N	FAULT IN PART OF READ W3 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I <u>INDICATORS I DISPLAY IREPLACE_ASSEMBLIES</u> I IND GDI XXXXQQQQQQIIAAAAA99	
37 14 37 15 37 16 37 17		SPARE SPARE SPARE SPARE	
37 18 1 37 19	T184	TEST RCEX, COMPARE => NO-GO Serially Load the B register with A0000300 Read & Compare the external memory word with A	
2	F184.1	FAULT LOC WITHIN TEST 184, NOT A PROGRAMMED STOP- RCEX LATCH NOT RESET	

		I TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
			IINDICATORSI_DISPLAYI	
	1	T184(CONT)	BRANCH TO MAJOR 37 MINOR 26 ON NO-GO	
37 20	2	T184.2	TEST FOR FAULT IN READ EXMW Compare the B register to A Branch to Major 37 minor 22 on NO-Go	
37 21	3	F184.2.G	REAC EXMW FAULT ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I	AACO37* S21
37 22	3	F184.2.N	FAULT IN RCEX IBT OR LATCH ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I	
37 23 37 24 37 25			SPARE SPARE SPARE	
37 26 37 27	1	T185	TEST RCM1, COMPARE => NO-GO RESET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST CIU CLOCK MODE (GTC003*) SERIALLY LOAD THE B REGISTER WITH AFFFFFE READ & COMPARE MISCELLANEOUS WORD 1 WITH A	
	2	F185.1	FAULT LOC WITHIN TEST 185, NOT A PROGRAMMED STOP- RCM1 LATCH NOT RESET	1
	1	T185(CONT)	SET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST NCU CLOCK MODE (GTCOO3*) BRANCH TO MAJOR 37 MINOR 34 ON NO-GO	
37 28	2	T185.2	TEST FOR FAULT IN READ MTW1 Compare the B register to A Branch to Major 37 Minor 30 on NO-Go	

TESTIDECISIO	ON   TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
37293	F185.2.G	READ MTW1 FAULT ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYI	I I AACO38* SƏ1
37303	F185.2.N	FAULT IN RCML IBT OR LATCH ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I	
			i
37 31 37 32 37 33		SPARE SPARE SPARE	
37 34 1 37 35	T186	TEST FOR FAULT IN PART OF READ MTW1 Compare the B register to Affff2 Branch to Major 37 minor 36 on ND-Go Branch to Major 37 minor 41	
37362	F186.N	FAULT IN PART OF READ MTW1 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I	!
		INO GOI_XXXXXXXQ11A1A4A20	1
37 37 37 38 37 39 37 40		SPARE SPARE SPARE SPARE	
37 41 1 37 42	T187	TEST RCPJ, COMPARE => NO-GO Serially Load the B register with Afffffff Read & Compare PJB Lines with A	
2	F187.1	FAULT LOC WITHIN TEST 187, NOT A PROGRAPMED STOP- RCPJ LATCH NOT RESET	r

	LEVEL	I TEST/FAULT	SELF-TEST PROGRAM	REMARKS
			I INDIGATORS I DISPLAY I REPLACE ASSEMBLIES	
	1	T187(CONT)	BRANCH TO MAJOR 37 MINOR 49 ON NO-GO	
7 43	2	T187.2	TEST FOR FAULT IN READ PJB Compare the B register to A Branch to Major 37 Minor 45 on NO-Go	
37 44	3	F187.2.G	READ PJB FAULT Enable vertical parity check Stop tape, display c register, nd-go light on	
			I_INDICATORSDISPLAYBEPLACE_ASSEMBLIESI IND_GOIBLANKIZA1AZAQ9I	AAC002* SƏ1
37 45	3	F187.2.N	FAULT IN RCPJ IBT OR LATCH ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYI	
37 46			SPARE	
87 47 87 48			SPARE SPARE	
87 49 87 50	1	T188	TEST RCM2, COMPARE => NO-GO Serially Load the B register with Affffeoo Read & Compare Hiscellaneous word 2 with a	
	2	F188.1	FAULT LOC WITHIN TEST 188, NOT A PROGRAMMED STOP- RCM2 LATCH NOT RESET	
			IINDICATORSDISPLAYREPLACE_ASSEMBLIESI IIESI_SEI_FAULT_IIOQQQQQIZAIAZAQ7I	
	1	T188(CONT)	BRANCH TO MAJOR 37 MINOR 57 ON NO-GO	
37 51	2	¥188.2	TEST FOR FAULT IN READ MTW2 Compare the B register to A Branch to Major 37 minor 53 on ND-Go	
37 52	3	F188.2.G	READ MTW2 FAULT Enable vertical parity check Stop Tape, display c register, no-go light on	

	LEVEL	I TEST/FAULT	I SELF-TEST PROGRAM	R EM ARK S
			IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GOIBLANKIZA1A2A17.91I	AACOO3* 501
7 53	3	F188.2.N	FAULT IN RCM2 IBT OR LATCH Enable vertical parity check Stop tape, display c register, ND-GO light on	
			IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI ING_GOI_177777000124142412.71	
7 54 7 55 7 56			SPARE - Spare Spare	
757 758	1	T189	TEST RCDW, COMPARE ≈> NO-GO Serially load the B register with A3218 Read & Compare discrete word with A	
	2	F189.1	FAULT LOC WITHIN TEST 189, NOT A PROGRAMMED STOP- RCOW LATCH NOT RESET	
			BRANCH TO MAJOR 37 MINOR 65 ON NO-GO	
7 59	2	T189.2	TEST FOR FAULT IN READ DOWD Compare the B register to A Branch to Major 37 minor 61 on ND-GO	
7 60	3	F189.2.G	READ DOWD FAULT ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
			INDICATORSDISPLAYREPLACE_ASSEMBLIESI	AAC004* SƏ1
7 61	3	F189.2.N	FAULT IN RCDW IBT OR LATCH Enable vertical parity check Stop tape, display c register, nd-go light on	

TESTIDECISION	TEST/FAULT  NUMBER	I SELF-TEST PROGRAM	I REMARKS
		IINDICATORSI_DISPLAY_IBEPLACE_ASSEMBLIESI IND_GOI_31030000012A1A2A(2.7)I	
62 63 64			
65 1	T190	TEST RMBA, MB->AREG PARALLEL, CREG -> WD1* DR -> NAD* REC -> AREG ON RMBA	
7 66		SERIALLY LOAD THE B REGISTER WITH A5555555	
		COMPARE THE 8 REGISTER TO F Initiate self test mode 2-load self test register with 8FBFFF0BFF	CREG=55555555 CREG->ROM, ROM->WD1 DR
		LOAD A REGISTER WITH OFFFFFF	
		READ THE MB LINES INTO THE A REGISTER	CREG=555555555->WD1 DR+ MB(NAD)REC->AREG = A55555
		COMPARE THE B REGISTER TO THE A REGISTER Branch to major 37 minor 69 on ND-GO Branch to major 37 minor 73	
67 68		SPARE SPARE	
69 2	T190.N	FAULT IN RMBA OR MB->AREG ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON	
		I_INDICATORS I DISPLAY IREPLACE ASSEMBLIES	
		NO GO   252525252124141404	RMBA IBT OR AREG CLK EN
		INO GO I 425252525212A1A1A17	IAD204 \$20
		INO GO I 425240000012A1A1A17 I	IRA055* S@1
		NO GO 1 2525212A1A1A17	IRA056* \$21
		INO_GOI_52525252511A1A4A16I INO_GOI2400000000012A1A1A12	INPUT TO GACOO9 SƏ1 Areg pe
			AREG PE
			AREG PE
		NO_GD1120000012A1A1A12	AREG PE
		IND_GDI5000012A1A1A11	AREG PE
		INO GOI240012A1A1A11I	AREG PE Areg pe
			AREG PE
7 70		SPARE	
7 71 7 72		SPARE SPARE	
37 73 1 37 74	T191	TEST RMBA => XTD104+=0 Serially load the B register with A	

TESTIDECISION   TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
	INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFOFEF LOAD A REGISTER WITH A0000800 READ THE MB LINES INTO THE A REGISTER COMPARE THE B REGISTER TO THE A REGISTER LOGICALLY "AND" C REGISTER AND A00008 - RESULT IN B & C #EGISTER BRANCH TO MAJOR 37 MINOR 77 ON NO-GO BRANCH TO MAJOR 37 MINOR 98	MTW2->RIM
37 75 37 76	SPARE SPARE	
37 77 2 F191.N	INPUT TO CACLOG SƏL Enable vertical parity Check Stop Tape, display C register, ND-go light on	
	INDICATORS I DISPLAY I BEPLACE ASSEMBLIES	1
37 78 37 79	SPARE SPARE	
37 80	SPARE	
37 81 37 82	SPARE SPARE	
37 83 37 84	SPARE SPARE	
37 85	SPARE	
37 86	SPARE	
37 87 37 88	SPARE SPARE	
37 89	SPARE	
37 90 37 91	SPARE SPARE	
37 92	SPARE	
37 93 37 94	SPARE SPARE	
37 95	SPARE	
37 96 37 97	SPARE SPARE	
37 98 37 99	ENABLE VERTICAL PARITY CHECK END OF MAJOR TEST	

TESTIDECISION	TEST/FAULT	I SELF-TEST PROGRAM	REMARKS
8 00 2	F30.10 F192.3	FAULT IN 658, 758, LSB OF MABC, UR CBC436* S@O	
		INDICATORS I DISPLAY I REPLACE ASSEMBLIES I IEST SET FAULT I2100000000011A1A1A121.231	
		PUNCH TAPE LEADER 12 INCHES LONG BRANCH TO MAJOR 38 MINOR 3	
88 01 88 02		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON Stop Tape, Display c register, NO-go light on	
8 03 1	T192	TEST 558 OF MABC & INPUT TO MBC061 Branch to Major 39 minor 2	
8 04		END OF MAJOR TEST	

TESTID	ECISION	I TEST/FAULT	I SELF-TEST PROGRAM	REMARKS
F2 F2	F30.11 F242.2 F282.1 F283.1	FAULT IN MABC		
			I INDICATORS I DISPLAY I REPLACE ASSEMBLIES I TEST. SET. FAULT I 210000000011A1A121+22+231	
			PUNCH TAPE LEADER 12 INCHES LONG Branch to major 39 minor 3	
9 01 9 02 9 03			STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON ENC OF MAJOR TEST	

TESTIDECISIO	N   TEST/FAULT LNUMBER	I SELF-TEST PROGRAM	RE MARK S
	************** * *	COMPUTER FLAGS CONTOL TESTS	***************************************
	*****	***************************************	*******
+0 00		INITIALIZE DEFINE SELF TEST TAPE SET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST NCU CLOCK MODE (GTCOO3+) ENABLE LOW LEVEL ON GTCOO1+ BRANCH TO MAJOR 40 MINOR 3	
0 01 0 02		STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON	
0 03 1 0 04	¥195	TEST SET I/O COMPLETE, GTCO10*=0 -> QUT009 PREVIOUS TEST = (38)T192 SET THE I/O COMPLETE FLAG (GTCO10*) READ & COMPARE MISCELLANEOUS WORD 1 WITH A LOGICALLY 'AND' C REGISTER AND A008 - RESULT IN B & C REGISTER BRANCH TO MAJOR 40 MINOR 5 ON NO-GO BRANCH TO MAJOR 40 MINOR 5	
0052	F195.N	FAULT IN SIDC         ENABLE VERTICAL PARITY CHECK         STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON         Implicators       1         INDICATORS       1         DISPLAY       1         REPLACE ASSEMBLIES       1         ING GO       1       200000011A1A4A08         I       1       1	
00 06 1 00 07	T196	RESET 1/O COMPLETE RESET THE 1/O COMPLETE FLAG (GTCO10*) READ & COMPARE MISCELLANEOUS WORD 1 WITH AOO8 LOGICALLY 'AND' C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS BRANCH TO MAJOR 40 MINOR 8 ON NO-GO BRANCH TO MAJOR 40 MINOR 12	
0082	F196.N	FAULT IN RIOC Enable vertical parity check Stop Tape, Display C register, NO-GO light on	

TESTIDECISION	I TEST/FAULT	SELF-TEST PROGRAM	REMARKS
		IINDICATORSI DI SPLAYREPLACE ASSEMBLIESI IND_GDI200000012A1A2A(12+17)I	
0 09 0 10 0 11		SPARE SPARE SPARE	
0121 013	¥197	TEST SET SERIAL I/O CONTROL, GTCO11*=0 -> QUTO10 SET THE SERIAL I/O CONTROL FLAG (GTCO11*) READ & COMPARE HISCELLANEOUS WORD 1 WITH A LOGICALLY *AND* C REGISTER AND A004 - RESULT IN B & C REGISTER BRANCH TO MAJOR 40 MINOR 14 ON NO-GO BRANCH TO MAJOR 40 MINOR 15	
0142	F197.N	FAULT IN SSID ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I <u>INDICATORS I DISPLAY I BEPLACE ASSEMBLIES</u> IND GO I 100000011A144008 I I2A1A2A12+17+20+221	
0151 016	T198	TEST RESET SERIAL I/O CONTROL RESET THE SERIAL I/O CONTROL FLAG (GTCO11*) READ & COMPARE MISCELLANEOUS WORD 1 WITH A004 LOGICALLY 'AND' C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS BRANCH TO MAJOR 40 MINOR 17 ON NO-GO BRANCH TO MAJOR 40 MINOR 21	
0172	F198.N	FAULT IN RSIO ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I INDICATORS I DISPLAY I REPLACE ASSEMBLIES	
0 18 0 19 0 20		SPARE Spare Spare	
0211 022	T 1 99	TEST SET SERIAL INPUT DATA, GTCO12*=0 -> QUTO11 SET THE SERIAL INPUT DATA FLAG (GTCO12*) READ & COMPARE MISCELLANEOUS WORD 1 WITH A LOGICALLY 'AND' C REGISTER AND A002 - RESULT IN B & C REGISTER BRANCH TO MAJOR 40 MINOR 23 ON NO-GO	

	ECISION	I TEST/FAULT	I SELF-TEST PROGRAM	REMARKS
			BRANCH TO MAJER 40 MINOR 24	
0 23	2	F199.N	FAULT IN SSID ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I INDICATORS I DISPLAY I REPLACE ASSEMBLIES INO GO I 40000011A1A4A08 I L2A1A2A12+17+20+221	
0 24 0 25	1	T200	TEST RESET SERIAL INPUT DATA RESET THE SERIAL INPUT DATA FLAG (GTCO12*) READ & COMPARE MISCELLANEOUS WORD 1 WITH A002 LOGICALLY *AND* C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS BRANCH TO MAJOR 40 MINOR 26 ON NO-GO BRANCH TO MAJOR 40 MINOR 30	
0 26	2	F200.N	FAULT IN RSID ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYREPLACE_ASSEMBLIESI IND_GDI40000012A1A2A112.24}	
027 028 029			SPARE SPARE SPARE	
0 30 0 31	1	T2 01	TEST INHIBIT MEMORY CONTROL, GTCO14**0 -> QUTO13 SET THE INHIBIT MEMORY CONTROL FLAG (GTCO14*) READ & COMPARE MISCELLANEOUS WORD 1 WITH A LOGICALLY 'AND' C REGISTER AND A0008 - RESULT IN B & C REGISTER BRANCH TO MAJOR 40 MINOR 32 ON NO-GO BRANCH TO MAJOR 40 MINOR 33	
0 32	2	F201•N	FAULT IN SINM ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATOBSI_DISPLAYI	
033 034	1	T2 02	IND GD I 100000 1A1A4A07 I IIA1A2A(6+11+12+16) RESET INHIBIT MEMORY CONTROL RESET THE INHIBIT MEMORY CONTROL FLAG (GTC014*) READ & COMPARE MISCELLANEOUS WORD 1 WITH A0008 LOGICALLY 'AND' C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS	

	LEVEL	TEST/FAULT	I SELF-TEST PROGRAM I	REMARKS
			BRANCH TO MAJOR 40 MINOR 35 ON NO-GO Branch to Major 40 minor 39	
0 35	2	F202.N	FAULT IN RINM Enable vertical parity check Stop tape, display C register, NO-GO light on	
			INDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GOII0000011A1A2A111.161I	
0 36 0 37 0 38			SPARE SPARE SPARE	
0 39 0 40	1	T2 03	SET INHIBIT PROCEED, GTC002*=0 -> QUT007 SET THE INHIBIT PROCEED FLAG (GTC002*) READ & COMPARE MISCELLANEOUS WORD 1 WITH A LOGICALLY 'AND' C REGISTER AND A02 - RESULT IN B & C REGISTER BRANCH TO MAJOR 40 MINOR 41 ON NO-GO BRANCH TO MAJOR 40 MINOR 42	
0 41	2	F203.N	FAULT IN SINP Enable vertical parity check Stop tape, display c register, NO-GO light on	
			I INDICATORS I DISPLAY I	
0 42 0 43	1	T2 04	RESET INHIBIT PRCCEED RESET THE INHIBIT PROCEED FLAG (GTCOO2*) READ & COMPARE MISCELLANEOUS WORD 1 WITH ⊅02 LOGICALLY *ANO'C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS BRANCH TO MAJOR 40 MINOR 44 ON NO-GO BRANCH TO MAJOR 40 MINOR 48	
0 44	2	F204.N	FAULT IN RINP Enable vertical parity check Stop tape, display c register, ND-GD light on	

TESTIDECISION	I TEST/FAULT	I SELF-TEST PROGRAM I	REMARKS
		IINDICATORSI_DI SPLAYIREPLACE_ASSEMBLIESI INQ_GOI1000000011A1A2A(10x16)I	
0 45 0 46 0 47		SPARE Spare Spare	
048 1 049	T205	TEST SET CLEAR-WRITE MEMORY, GTC021*=0 -> QUT016 SET THE CLEAR WRITE MEMORY FLAG (GTC021*) READ & COMPARE WISCELLANEOUS WORD 1 WITH A LOGICALLY 'AND' C REGISTER AND A0001 - RESULT IN B & C REGISTER BRANCH TO MAJOR 40 MINOR 50 ON NO-GO BRANCH TO MAJOR 40 MINOR 51	
0502	F205.N	FAULT IN SCWM ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		<u>INDICATORS   DISPLAY_IREPLACE_ASSEMBLIES</u>    ND GO   10000 1A1A4A05      	
0511 052	T206	TEST RESET CLEAR-WRITE MEMORY RESET THE CLEAR WRITE MEMORY FLAG (GTCO21*) READ & COMPARE MISCELLANEOUS WORD 1 WITH A0001 LOGICALLY *AND* C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS BRANCH TO MAJOR 40 MINOR 53 ON NO-GO BRANCH TO MAJOR 40 MINOR 57	
0532	F206.N	FAULT IN RCWM ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON INDICATORS I DISPLAY I	
0 54 0 55		I <u>NO_GOI1000011A1A2A(111+16)</u> Spare Spare	
0 56		SPARE	
0571 058	T207	TEST SET INHIBIT INCREMENT CP,GTC003*=0 -> QUT008 SET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST NCU CLOCK MODE (GTC003*) READ & COMPARE MISCELLANEOUS WORD 1 WITH A LOGICALLY 'AND' C REGISTER AND A01 - RESULT IN B & C REGISTER	

	LEVEL	TEST/FAULT	SELF-TEST PROGRAM	REMARKS
			BRANCH TO MAJOR 40 MINOR 59 ON NO-GO Branch to Major 40 minor 60	
059	2	F207.N	FAULT IN SIIC Enable vertical parity check Stop tape, display c register, no-go light on	
			IINDICATORSI_DISPLAY_IBEPLACE_ASSEMBLIESI NO GO I 4000000 1A1A4A09 II1A1A2A(10,11.16)	
0 60 0 61	1	T2 08	TEST RESET INHIBIT INCREMENT CP RESET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST CIU CLOCK MODE (GTC003#) READ & COMPARE MISCELLANEOUS WORD 1 WITH A01 LOGICALLY 'AND' C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS BRANCH TO MAJOR 40 MINOR 62 ON NO-GO BRANCH TO MAJOR 40 MINOR 66	
0 62	2	F208.N	FAULT IN RIIC ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I INDICATORS I DISPLAY I REPLACE ASSEMBLIES IND_GOI \$00000011A1A2A(11:16)	
0 63 0 64 0 65			SPARE SPARE SPARE	
0 66 0 67	1	T2 09	TEST SET INITIATE INSTRUCTION CYCLE SET THE INITIATE INSTRUCTION CYCLE FLAG (GTCO2O*) READ & COMPARE MISCELLANEOUS WORD 1 WITH A LOGICALLY *AND' C REGISTER AND A0004 - RESULT IN B & C REGISTER BRANCH TO MAJOR 40 MINOR 68 ON NO-GO BRANCH TO MAJOR 40 MINOR 69	
0 68	2	F209.N	FAULT IN SINC Enable vertical parity check Stop tape, display c register, no-go light on	

NO.L_LEVEL	TEST/FAULT LNUMBER	I SELF-TEST PROGRAM	REMARKS 
		IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI INO GO I 40000 1A1A4A07 IIA1A2A(11&14×16)I	
40 69 1 40 70	T210	TEST RESET INITIATE INSTRUCTION CYCLE RESET THE INITIATE INSTRUCTION CYCLE FLAG (GTCO2O*) READ & COMPARE MISCELLANEOUS WORD 1 WITH A0004 LOGICALLY 'AAND' C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS BRANCH TO MAJOR 40 MINOR 71 ON ND-GO BRANCH TO MAJOR 40 MINOR 75	
60712	F210.N	FAULT IN RINC ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI INO_GO400000011A1A2A(14+16)I	
40 72 40 73 40 74		SPARE SPARE SPARE	
40 75 1 40 76	7211	TEST SET INCREMENT CP, GTC022*=0 -> QUT017 SET THE INCREMENT CP FLAG (GTC022*) READ & COMPARE MISCELLANEOUS WORD 1 WITH A LOGICALLY 'AND' C REGISTER AND A00008 - RESULT IN B & C REGISTER BRANCH TO MAJOR 40 MINOR 77 ON ND-GO BRANCH TO MAJOR 40 MINOR 78	
60772	F211.N	FAULT IN SICP ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON I INDICATORS I DISPLAY I REPLACE ASSEMBLIES INO GO I 400011A1A4A04 IIAIA2A(10,11,17)	1
+078 1 +079	T212	TEST RESET INCREMENT CP RESET THE INCREMENT CP FLAG (GTCO22*) READ & COMPARE MISCELLANEOUS WORD 1 WITH A00008 LOGICALLY 'AND' C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS BRANCH TO MAJOR 40 MINOR 80 ON NO-GO BRANCH TO MAJOR 40 MINOR 84	
40 80 2	F212.N	FAULT IN RICP	

TESTICECISION	I TEST/FAULT	SELF-TEST PROGRAM	REMARKS
		ENABLE VERTICAL PARITY CHECK Stop Tape, Display C register, NO-GO light on	
		I INDICATORS I DISPLAY I REPLACE ASSEMBLIES	
0 81		SPARE	
082 083		SPARE SPARE	
0 84 1	T213	TEST GENERATE COMPUTER INTERUPT XTW135*=0 -> QUT019	
085		XTW136*=1 -> QUTO20 ENABLE COMPUTER RESET (GTCO00*) GENERATE COMPUTER INTERRUPT WITH CODE OF 2 SIGNAL ON IS XTW136* READ & COMPARE MISCELLANEOUS WORD 1 WITH A00001 LOGICALLY 'AND' C REGISTER AND A00003 - RESULT IN B & C REGISTER BRANCH TO MAJOR 40 MINOR 86 ON NO-GO BRANCH TO MAJOR 40 MINOR 87	
0862	F213.N	FAULT IN GINT OR XTN135*->QUT019 Enable vertical parity check Stop tape, display c register, no-go light on	
		INDICATORS         I_DISPLAY         BEPLACE         ASSEMBLIES         I           IND GO         I         1000[1A1A2A(4,10,12,13,14)         I           I         I1A1A5A84         I           IND GO         I         1000[1A1A2A(4,10,12,13,14)         I	KTW126
0871 088	T214	TEST RESET OF INTERUPT REQUESTS SET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST NCU CLOCK MODE (GTC003*) ENABLE CONTROLLED TIMING PULSE INTERVAL 10 ON GTC001* READ & COMPARE MISCELLANEOUS WORD 1 WITH A00003 LOGICALLY 'ANO' C REGISTER AND A00003 - RESULT IN B & C REGISTER BRANCH TO MAJOR 40 MINOR 89 ON NO-GO BRANCH TO MAJOP 40 MINOR 90	
0892	F214.N	FAULT IN RESET OF INTERUPT REQUESTS ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	

NO.L_LEV	ION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
		I_INDICATORSI_DISPLAY1REPLACE_ASSEMBLIES	   KTW125
0901	T215	TEST GENERATE COMPUTER INTERUPT XTW135*=1 -> QUT019	
0 91		XTM136*=0 -> QUTO20 ENABLE COMPUTER RESET (GTCO00*) GENERATE COMPUTER INTERRUPT WITH CODE OF 1 SIGNAL ON IS XTW135* READ & COMPARE MISCELLANEOUS WORD 1 WITH A00002 LGGICALLY *ANO' C REGISTER AND A00003 - RESULT IN B & C REGISTER BRANCH TO MAJOR 40 MINOR 92 ON NO-GO BRANCH TO MAJOR 40 MINOR 93	
0922	F215.N	FAULT IN XTW136*->QUTO19 OR KTW125 Enable vertical parity check Stop tape, display c register, no-go light on	
		IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES NO_GOI1000I1A1A2A(4,10) NO_GOI400[1A1A2A(4,10,14) II1A1A4A03	   KTW125   
0931 094	T216	TEST RESET OF KTW126 ENABLE CONTROLLED TIMING PULSE INTERVAL 10 ON GTC001* READ & COMPARE MISCELLANEOUS WORD 1 WITH A00003 Logically "And" C Register and A00003 - Result in B & C Register Branch to Major 40 Mindr 95 on NO-GD Branch to Major 40 Mindr 98	
0952	F216.N	FAULT IN RESET OF KTW126 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	-,
		I NO_GOI40011A1A2A10	.i
0 96 0 97		SPARE SPARE	
, 098 099	-	ENABLE VERTICAL PARITY CHECK End of Major test	

TESTICECISION   TEST	/FAULT   MBER	SELF-TEST PROGRAM	REMARKS
1_00A166366100	DU <u>CD</u> t	~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~	
41 00	BRANCH TO P	AAJOR 41 MINOR 3	
41 01	STOP TAPE,	DISPLAY C REGISTER, NO-GO LIGHT ON	
41 02	STOP TAPE,	DISPLAY C REGISTER, NO-GO LIGHT ON	
41 03	END OF MAJO	DR TEST	

,

TESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
<i>(</i> <b>a a a</b>		
42 00	BRANCH TO MAJOR 42 MINOR 3	
42 01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
42 02	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
42 03	END OF MAJOR TEST	

STOP	TAPE,	DISPLAY	C	REGISTER,	NO-GO	LIGHT	<b>GN</b>
			С	REGISTER,	NO-60	LIGHT	ON
END	DE MAJO	OR TEST					

TESTIDECISION   TEST/FAULT	SELF~TEST PROGRAM	I REMARKS I
43 00 43 01 43 02 43 03	BRANCH TO MAJOR 43 MINOR 3 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON END OF MAJOR TEST	

TESTIDECISION   TEST/FAU		I REMARKS I
44 00	BRANCH TO NAJOR 44 MINOR 3	
<b>44 01</b> 1 T282	TEST INPUT TO MBCO61 FOR SƏ1 Previous test = (52)1281 Branch to Major 53 minor 2	
44 02 44 03	STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON END OF MAJOR TEST	

	LEVEL	I TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
		**********		*******
		* * * *****	TESTS OF EIP / EOP CONTROL - MAJORS 45 & 46 TESTS T220 - T242	- + + *
5 00			INITIALIZE DEFINE SELF TEST TAPE SET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST NCU CLOCK MODE (GTC003*) ENABLE LOW LEVEL ON GTC001* BRANCH TO MAJOR 45 MINOR 3	
5 01	2	F281.1	BBC739* SƏ1 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
			IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES IND_GOIBLANKIIAIAIA(21,23)	
5 02			STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
5 03 5 04	1	T 2 20	TEST EIP 1350 I/O CMPLT -> RESET TST2(SIM NO-GO), BREG -> EB SERIAL PREVIOUS TEST = (40)T216 SERIALLY LOAD THE B REGISTER WITH AAAAAAAA INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF4FFF LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH ABA200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH ABA000 BRANCH TO MAJOR 45 MINOR 5 ON NO-GO	SIM NO-GO Ea =1350 Activate I/O Req
	2	F220.1	FAULT LOC WITHIN TEST T220 - EIP/EOP CONTROL MALFUNCTION         I       INDICATORS       I DISPLAY       REPLACE ASSEMBLIES         I TEST SET FAULT I       40000012A1A1A05       IEST SET FAULT I       20010012A1A2A(12:13:17:18:20:21)         I TEST SET FAULT I       10012A1A1A05       IEST SET FAULT I       10012A1A1A05         I TEST SET FAULT I       10012A1A1A05       IEST SET FAULT I       10012A1A1A05	
	1	T220(CONT)	BRANCH TO MAJOR 45 MINOR 24	-
5 05 5 06	2	T220.2	TEST EOP 0370 I/O CMPLT -> RESET TST2(SIM NO-GO) LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3E200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3E000 BRANCH TO MAJOR 45 MINOR 1 BRANCH TO MAJOR 45 MINOR 11	EA = 0370 Activate i/o req

		I TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
45 07	3	F220.2.N	FAULT IN EA DECODES OR SYNCHRONIZED I/O REQ ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
			IINDICATORSI_DISPLAY_IBEPLACE_ASSEMBLIES INC_GOBLANKI2AJA2A113.14.15.161	CECO99 NOT ACTIVE
45 08 45 09 45 10 45 11			SPARE SPARE SPARE SPARE	
45 12	3	T220.2.G	TEST EOP 0351 I/O CMPLT -> RESET TST2 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3A600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3A400 BRANCH TO MAJOR 45 MINOR 13 ON NO-GO	EA≖0351 Activate I/O Req
	4	F220.2.GG	FAULT IN EIP 1350 DECODE OR LATCH ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I INDIGATORS I DISPLAY I REPLACE ASSEMBLIES	AEC035* SƏ1 OR IEC046* SƏ1
45 13 45 14	4	T220.2.GN	IND_GOIBLANK12A1A2A(15+16+17+18) TEST EOP 0352 I/O CMPLT -> RESET TST2 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3AA00 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3AB00 BRANCH TO MAJOR 45 MINOR 15 ON NO-GO	EA=0352 ACTIVATE I/O REQ
	5	F220.2.GNG	FAULT IN AECO47->1/0 CMPLT ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON INDICATOBSI DISPLAY. IBEPLACE ASSEMBLIES	   AEC491* S∂1
45 15	5	F220.2.GNN	FAULT IN EA DECOCE LOGIC ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I	I I IED051 OR IED037
45 16 45 17 45 18 45 19 45 20			SPARE SPARE SPARE SPARE SPARE	

TESTIDE		I TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
5 21 5 22 5 23			SPARE SPARE SPARE	
45 24 45 25	1	T221	TEST DATA TRANSFER OF EIP 1350 IN T220, SERIAL Breg->GTC012#->QUB000->Breg 28 bits. Compare the B register to 05555555	TEST FOR 28 BITS INVERTED, MSHD NOT TRANSFERED
	2	F221.1	FAULT LOC WITHIN TEST T221- DATA SATURATED BREG I <u>INDICATORS</u> I DISPLAY I <u>BEPLACE ASSEMBLIES</u> I TEST SET FAULT I 2000/2A1A1A20 I <u>I I I I I I I I I I I I I I I I I I </u>	NR6121*
	1	T221(CONT)	BRANCH TO MAJOR 45 MINOR 26 ON NO-GO Branch to Major 45 minor 37	
5 26 5 27	2	1221.2	TEST FOR NO "END 28 BITS" Compare the B register to 5555555 Branch to Major 45 Minor 28 on NO-Go	
	3	F221.2.G	FAULT IN "END 28 BITS" ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I INDICATOBS I DISPLAY I REPLACE ASSEMBLIES INO GO I BLANK [2A1A1A05 I	KEC232* S@1
45 28 45 29	3	T221.2.N	TEST FOR DATA TO EB SƏ1 Compare The B register to offffff Branch to Major 45 Minor 30 on ND-go	
	4	F221.2.NG	FAULT IN BREG->GTC012*->QUB000->BREG, DATA SƏ1 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I <u>INDICATORS I DISPLAY I REPLACE ASSEMBLIES</u> NO GO I BLANK (2A1A1A20 I	QUB000 501
45 30 45 31	4	T221.2.NN	TEST FOR FAULT IN INHIBIT BREG END AROUND COMPARE THE B REGISTER TO AFFFFFF BRANCH TO MAJOR 45 MINOR 32 ON NO-GO	
	5	F221.2.NNG	NO INHIBIT OF BREG SHIFT END AROUND => BREG<-BREG+GTC012*	

		1 TEST/FAULT	SELF-TEST PROGRAM	1 REMARKS 1
			ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I <u>INDIGATORS I DISPLAY I BEPLACE ASSEMBLIES</u> INO GO I BLANK IZAIAIAZO II	AEC531* SƏl
45 32 45 33	5	T221.2.NNN	TEST FOR NO CHANGE TO BREG DATA Compare the B register to Aaaaaaaa Branch to Major 45 minor 34 on No-go	
	6	F221.2.NNN >G	FAULT IN SHIFT CLOCKS TO BREG ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I INDIGATORS	AEC226* SƏ1
45 34 45 35	6	T221. 2. NNN >N	TEST FOR FAULT IL "EOP MODE SER DATA EN" Compare the 8 register to F5555555 Branch to Major 45 minor 36 on NO-Go	
	7	F221.2.NNN >NG	KEC232* INPUT TO AEC214* S21 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I INDIGATORS I DISPLAY I	1
45 36	7	F221.2.NNN >NN	NOT A NORMAL FAULT LOCATION ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I <u>INDICATORS I DISPLAY I BEPLACE ASSEMBLIES</u> NO GO IXXXXXXXXI2AIA2A(1,8,13,16,17,21) I OR I LOR I L2AIA2A(12,18,20]	
45 37 45 38	1	T222	TEST EIP 1341 I/C CMPLT -> RESET TST2(SIM ND-GD), AREG(TAPE)->EB SERIAL INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF4FFF LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH AB8600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH AB8400 LOAD EIP DATA FIELD 555555 INTO A REGISTER	SIM NO-GO EA=1341 Activate I/O Req Only 6 Data Char to test

TESTICECISION	TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
2	F222.1	FAULT LOC WITHIN TEST T222- EIP 1341 LATCH NOT RESET	CLEAR OF AREG
1	T222(CONT)	BRANCH TO MAJOR 45 MINOR 39 ON NO-GO BRANCH TO MAJOR 45 MINOR 46	•
5392 540	T222.2	TEST EIP 1340 I/O CMPLT -> RESET TST2(SIM NO-GO) LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH AB8200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH AB8000 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) /ITH B8200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH B8000 BRANCH TO MAJOR 45 MINOR 41 ON ND-GO	EA=1340 ACTIVATE I/O REQ EA = 1340 ASSUMING SRT DAT EN ACTIVE ACTIVATE I/O REQ
3	F222.2.G	FAULT IN EIP 1341 DECODE OR LATCH, OR DEIP IBT OR LATCH ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I INDICATORS	I   AEC062* \$@1
5413	F222.2.N	FAULT IN EA DECODE LOGIC ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I <u>INDICATORS I DISPLAY I REPLACE ASSEMBLIES</u> NO GO I BLANK IZAIAZA(14:15,16)	1   1ED050
5 42 5 43 5 44 5 45		SPARE SPARE SPARE SPARE	
5 46 1	T223	TEST DATA TRANSFER OF EIP 1341 IN T222, SERIAL Areg->gubood=>breg 28 bits Compare the B register to Qaaaaaaf	TEST FOR 28 BITS FROM AREG
2	F123.1	FAULT LOC WITHIN TEST T223- DATA TO BREG SATURATED	INVERTED TO BREG

		N I TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
			I INDICATORS I DISPLAY I REPLACE ASSEMBLIES	   CEC238* Sa0
	1	T223(CONT)	BRANCH TO MAJOR 45 MINOR 48 ON ND-GO Branch to Major 45 minor 61	
45 48 45 49	2	T223.2	TEST FOR DATA -> EB SAL Compare the B register to offffff Branch to Major 45 Minor 50 on NO-GD	
	3	F223.2.G	DATA -> EB SƏL ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
			IINDICATORSDISPLAY	   AEC215* OR CEC238* SƏ1 
45 50 45 51	3	T223.2.N	TEST FOR NO CHANGE TO BREG DATA Compare the B register to 05555555 Branch to Major 45 minor 52 on NO-Go	BIT PATTERN IN BREG AFTEF T220
	4	F223.2.NG	FAULT IN EN OF BREG CLOCK Enable vertical parity check Stop tape, display c register, ND-go light on	
			I INDICATORS I DISPLAY I REPLACE ASSEMBLIES	   OPEN INPUT TO AEC216
5 52 5 53	4	T223.2.NN	TEST FOR NO CLEAR OF AREG Compare the B register to Qaaaaaaa Branch to major 45 minor 54 on ND-GO	
	5	F223.2.NNG	FAULT IN "CLEAR A #3" Enable vertical parity check Stop Tape, display c register, no-go light on	

TESTICECISIO	N I TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
		I INDICATORS I DISPLAY I REPLACE ASSEMBLIES	_  _  INPUT TO CEC213 OPEN
i <b>5 54</b> 5	F223.2.NNN	FAULT IN "EIP SHCRT DATA EN" OR NOT A NORMAL FAULT LOCATION ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	-1
		IND GO IXXXXXXXXXI2AIAIAO4 III2AIA2AI16,20,22,23,25) IND GOI12012AIAIA28	I LI LI OPEN INPUT TO CRA121
45 55 45 56 45 57 45 58 45 59 45 60		SPARE SPARE SPARE SPARE SPARE SPARE	
5 61 1 5 62	T224	TEST EIP 1340 I/O CMPLT -> RESET TST2(SIM NO-GO), AREG -> EB SERIAL SERIALLY LOAD THE B REGISTER WITH AAAAAAAA INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF4FFF LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH AB8200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH AB8000 BRANCH TO MAJOR 45 MINOR 63 ON NO-GO	SIM NO-GO Ea=1340 Activate i/o req
2	F224.1	FAULT LOC WITHIN TEST T224- EIP 1340 LATCH NOT RESET I_INDICATORSDISPLAYREPLACE ASSEMBLIES IEST_SET_FAULT_I200100120102010 IEST_SET_FAULT_I100120102010	- - - - - -
1	T224(CONT)	BRANCH TO MAJOR 45 MINOR 67	
<b>45 63 2</b>	F224.2	FAULT IN EIP 1340 DECODE OR LATCH ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON I INDICATORS I DISPLAY I	-  _  AEC034+ SƏ1
45 64 45 65 45 66		SPARE SPARE SPARE	
\$5 67 1	T225	TEST DATA TRANSFER OF EIP 1340 IN T224, AREG->GTC012*->QUB000->BREG	

		TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
5 68			COMPARE THE B REGISTER TO 047FFFFF Branch to Major 45 minor 69 on NO-GO	TEST FOR INVERTED EA 1340 Code from Areg
			BRANCH TO MAJOR 45 MINOR 73	
5 69	2	F225.N	FAULT IN DATA TRANSFER AREG->EB Enable vertical parity check Stop tape, display c register, ND-G0 light on	
			I INDICATORS I DISPLAY I BEPLACE ASSEMBLIES	OPEN INPUT TO AECO44
5 70 5 71 5 72			SPARE SPARE SPARE	
5 73 5 74	1	T226	TEST EIP 1360 I/O CMPLT -> RESET TST2(SIM NO-GO), CREG -> EB SERIAL INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF4FFF LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH ABC200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH ABC200 BRANCH TO MAJOR 45 MINOR 75 ON NO-GO	SIM NO-GO Ea=1360 Activate I/O Req
	2	F226.1	FAULT LOC WITHIN TEST T226- EIP 1360 LATCH NOT RESET I <u>INDICATORS I DISPLAY I BEPLACE ASSEMBLIES</u> I IEST SET FAULT I <u>20010012A1A2A18</u> IIEST SET FAULT <u>10012A1A2A18</u>	
	1	T226(CONT)	BRANCH TO MAJOR 45 MINOR 78	
i5 75	2	F226.2	FAULT IN EIP 1360 DECODE OR LATCH ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I INDICATORS I DISPLAY I REPLACE ASSEMBLIES IND GO	AEC036* SƏ1
45 76 45 77			SPARE SPARE	
45 78	1	T227	TEST DATA TRANSFER OF EIP 1360 IN T226, CREG->GTCO12*->QUBOOO->BREG, 28 BITS ONLY	
45 79			SERIALLY LOAD THE B REGISTER WITH AAAAAAAO	°CREG = AAAAAAAA Ea=1360 Activate I/O Req

	ECISION	1 TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
	2	F227.1	FAULT LOC WITHIN TEST T227- DATA FROM CREG TO BREG SATURATED I INDICATORS I DISPLAY I REPLACE ASSEMBLIES I TEST SET FAULT. 2000124142422	CEC218* \$ @0
	1	T227(CONT)	BRANCH TO MAJOR 45 MINOR 80 ON NO-GO Branch To Major 45 minor 86	
580	2	F227.2	FAULT IN TRANSFER OF DATA CREG -> EB ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON 	AEC217* OR CEC218* S@1
			112A1A2A120.22.241	
5 81 5 82 5 83 5 84 5 85			SPARE SPARE SPARE SPARE SPARE	
586 587	1	T228	TEST EOP 0351 1/0 CMPLT -> RESET TST2(SIM NO-GO), EB -> BREG SERIAL SET THE SERIAL INPUT DATA FLAG (GTC012*) INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF4FFF LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3A600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3A400 BRANCH TO MAJGR 45 MINOR 88 ON NO-GO RESET THE SERIAL INPUT DATA FLAG (GTC012*)	SIM EB = 0000000 SIM NO-GO EA = 0351 ACTIVATE I/O REQ
	2	F228.1	FAULT LOC WITHIN TEST T228- EOP 0351 RESET MALFUNCTION I	BEC252* \$@1
	1	T228(CONT)	BRANCH TO MAJOR 45 MINOR 92	
588	2	F228.2	FAULT IN EOP 0351 DECODE OR LATCH ENABLE VERTICAL PARITY CHECK RESET THE SERIAL INPUT DATA FLAG (GTC012*) STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	

NQ.L.		N I TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
			IINDICATORSI_DISPLAYI	AEC037* Sal
589 590 591			SPARE SPARE SPARE	
592 593	1	T229	TEST DATA TRANSFER DF EDP 0351 IN T228, SSID=>GTC012*=0->QUB000->BREG, MSHD=A AFTER SHIFT COMPARE THE B REGISTER TO A	
	2	F229.1	FAULT LOC WITHIN TEST T229- DATA EB -> BREG SATURATED	AEC028* 5al
	1	T229(CONT)	BRANCH TO MAJOR 45 MINOR 94 ON NO-GO Branch to Major 45 minor 98	
594	2	F229.2	FAULT IN EB -> BREG DATA TRANSFER ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI DISPLAYI	INPUT TO AEC521 OPEN
595 596 597			SPARE SPARE SPARE	
598			ENABLE VERTICAL PARITY CHECK END OF MAJOR TEST	

	LEVEL	TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
46 00			INITIALIZE DEFINE SELF TEST TAPE SET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST NCU CLOCK MODE (GTC003*) ENABLE LOW LEVEL ON GTC001* BRANCH TO MAJOR 46 MINOR 3	
46 01 46 02			STOP TAPE, DISPLAY C REGISTER, NO-GD LIGHT ON STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
46 03 46 04	1	T230	TEST EOP 0356 I/O CMPLT -> RESET TST2, PAB REC -> BREG THEN BREG -> DIMR LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3BA00 SERIALLY LOAD THE B REGISTER WITH A3BB	EA = 0356 LOAD BREG WITH EA 0356 CODE AND I/O REQ FOR TRANS TO DIHR ON NEXT LOSI
			INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH 8FBFFF47FF	BREG->ROM, ROM->WD1+DR, SIM
			LOAD DISCRETE-INPUT WORD (EIP/EOP CODE) WITH AFA58 Branch to Major 46 minor 5 on No-Go Branch to Major 46 minor 11	NO-GO Data->WD1* DR on "Pjb->8"
46 05 46 06	2	T230+N	TEST EOP 0370 1/0 CMPLT -> RESET TST2(SIM NO-GO) INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF4FFF LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3E200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3E200 BRANCH TO MAJOR 46 MINOR 7 ON NO-GO	SIM NO-GO EA = 0370 I/O REQ
	3	F230.NG	FAULT IN ECP 0356 => SHORT I/O CMPLT LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT DN	
			I INDICATORS I DISPLAY I REPLACE ASSEMBLIES	IEC069* \$21
46 07	3	F230.NN	FAULT IN "SHORT I/O CMPLT" LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	

		I TEST/FAULT	SELF-TEST PROGRAM	1 REMARKS 1
			IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GOIBLANKI2A1A2A11+12+13+16}I	AEC089* SƏ1
6 08 6 09 6 10			SPARE SPARE SPARE	
6 11 6 12	1	T231	TEST PARALLEL DATA TRANSFER IN T230, TEST FOR DIHR <- AA500 <- AREG=AA580 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFF0FEF COMPARE THE B REGISTER TO AFAS LOGICALLY 'AND' C REGISTER AND AFFFF4 - RESULT IN B & C REGISTER BRANCH TO MAJOR 46 MINOR 13 ON NO-GO BRANCH TO MAJOR 46 MINOR 23	MTW2->RIM
6 13 6 14	2	T231.N	TEST FOR NO "EN PJB -> BREG" Compare the B register to A3ea74 Branch to Major 46 minor 15 on ND-Go	
	3	F231.NG	FAULT IN "EN PJB -> BREG " LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
				TEC332* Sal
6 15 6 16	3	T231.NN	TEST FOR NO INHIRIT BREG -> ROM DURING PJB -> BREG Compare the B register to AC158 Branch to Major 46 minor 17 on ND-Go	
	4	F231.NNG	FAULT IN INHIBIT OF BREG -> ROM FROM S.T. CONTROL REG LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
			IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GOIBLANKIZAIAIAQ7I	INPUT TO AYR744* OPEN
6 17 6 18	<b>4</b>	T231.NNN	TEST FOR NO EN PJB -> RIM Compare the B register to A05AF4 Branch to Major 46 minor 19 on ND-Go	
	5	F231.NNNG	FAULT IN EN PJB -> RIM	

ESTICECISION	I TEST/FAULT	SELF-TEST PROGRAM	T REMARKS
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I INDICATORS I DISPLAY I REPLACE ASSEMBLIES IND GD I BLANK IZA1AZA09	I I input to AAE211 Open
5 19 5	F231.NNNN	NOT A NORMAL FAULT LOC - FAULT IN EOP 0356 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I INDICATORS I DISPLAY I REPLACE ASSEMBLIES IND GO IXXXXXXXXXI2A1A2A(12.14.15.16.20.26)	1
5 20 5 21 5 22		SPARE SPARE SPARE	
5 23 1 5 24	T232	TEST EOPO353 I/O CMPLT -> RESET TST2(SIM NO-GO), PJB -> BREG PARALLEL SERIALLY LOAD THE B REGISTER WITH A INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH 8FBFFF4FFF LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3AEOO LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3AEOO BRANCH TO MAJOR 46 MINOR 25 ON NO-GO BRANCH TO MAJOR 46 MINOR 29	ROM->WD1* DR, SIM NO-GO EA = 0353 I/O REQ, DATA -> ROM
5 25 2	F232•N	FAULT IN EOP 0353 DECODE -> SHORT I/O CMPLT LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORS1_DISPLAY1	   BED253* Sal
6 26 6 27 6 28		SPARE Spare Spare	
6291 630	T233	TEST DATA TRANSFER IN T232 Compare the B register to ac53ffff Branch to Major 46 minor 31 on NO-Go Branch to Major 46 minor 35	
6312	F233.N	FAULT PJB -> BREG OF EOP 0353 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A ENABLE VERTICAL PARITY CHECK	

TESTIDECIS	ION   TEST/FAULT ELNUMBER	SELF-TEST PROGRAM	REMARKS
		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		I	AECO19
			ACCOLA
6 32		SPARE	
6 33		SPARE	
6 34		SPARE	
6 35 1	T2 34	TEST EOP 0352 I/C CMPLT -> RESET TST2(SIM ND-GO), JEB -> BREG PARALLEL	
6 36		SERIALLY LOAD THE B REGISTER WITH AFFFFFF	
		INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH 2F8FFF4FFF	ROM->MB DR, SIM NO-GO
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH ABAAOO	EA=0352
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3A800 Branch to Major 46 minor 37 on no-go	I/O REQ
		BRANCH TO MAJOR 46 MINOR 41	
6 37 2	F234+N	FAULT IN EOP 0352 DECODE -> SHORT 1/0 CMPLT	
0 57 2	123401	LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A	
		ENABLE VERTICAL PARITY CHECK Stop Tape, display c register, no-go light on	
		IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES	1
		INO_GOIBLANKI2A1A2A(1.12.15)	BED252* SƏ1
6 38		SPARE	
6 39		SPARE	
6 40		SPARE	
6 4 1 1	T235	TEST DATA TRANSFER IN T234	
6 42		COMPARE THE B REGISTER TO A3A8	
		BRANCH TO MAJOR 46 MINOR 43 ON NO-GO	
		BRANCH TO MAJOR 46 MINOR 51	
6432	T235.N	TEST FOR NO DATA TRANSFER => BREG UNCHANGED	
6 44		COMPARE THE B REGISTER TO AFFFFFF	
		BRANCH TO MAJOR 46 MINOR 45 ON NO-GO	
3	F235.NG	FAULT IN JEB -> BREG	
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A	
		ENABLE VERTICAL PARITY CHECK Stop tape, display c register, nd—gd light on	
		STOR TARLY DESIGNT & REGISTERT NU-BU LIGHT ON	

TESTICECISION	I TEST/FAULT	I SELF-TEST PROGRAM	R EM ARK S
		I <u>INDICATÓRS I DISPLAY I REPLÀCE ASSEMBLIES</u> INO GO I BLANK IZAIAIAO3 I IZAIAZA(16+ZO)	-     AEC311* SƏ1 _
6453 646	T235.NN	TEST FOR NO EN JEB -> INMX Compare the B register to A Branch to Major 46 Minor 47 on NO-Go	
4	F235.NNG	FAULT IN EOP 0352 EN JEB -> INMX Load discrete input word (EIP/EOP Code) with a Enable vertical parity creck Stop tape, display c register, no-go light on	
		IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES NO_GOIBLANKIIAIA4A19	_  _  INPUT TO CAC101 OPEN
+6 47   4	F235.NNN	NOT A NORMAL FAULT LOCATION - FAULT IN IN EOP 0352 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	-,
		IINDICATORSI_DISPLAYIRPPLACE_ASSEMBLIES INO_GOIXXXXXXXXXXI2A1A2A(1.12.14.15.16.20)	-'
46 48 46 49 46 50		SPARE SPARE SPARE	
46 51 1 46 52	T236	TEST EOP 0371·1/O CMPLT -> RESET TST2(SIM NO-GO), STOP COMPUTER CLOCK Initiate self test mode 2-load self test register with ofbfff4fff Enable continuous high level on gtcool*	SIM NO-GO
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3E600 Load discrete input word (Eip/Eop Code) with A3E400 Branch to Major 46 minor 53 on ND-GO Branch to Major 46 minor 59	EA=0371 I/O REQ
46532 4654	T236.N	TEST EOP 0370 I/O CMPLT -> RESET TST2(SIM NO-GO) LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3E200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3E000 ENABLE LOW LEVEL ON GTCOOI+ BRANCH TO MAJOR 46 WINOR 55 ON NO-GO	EA=0370 I/D REQ
3	F236.NG	FAULT IN EOP 0371 DECODE -> SHORT [/O CMPLT LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A	

TESTIDECISION	I TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
		ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		INO_GOIBLANK12A1A2A11.121	CED270* Sal
6553	F236.NN	FAULT IN EA DECODE NET LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		INDICATORS L DISPLAY I REPLACE ASSEMBLIES	IED053 OR IED137 Sao
6 56 6 57		SPARE SPARE	
6 58		SPARE	
6591 660	T237	TEST FOR RESET OF GTC001* TO 0 IN T236 - READ & COMPARE MISCELLANEOUS WORD 1 WITH A LOGICALLY "AND" C REGISTER AND A00000C - RESULT IN B & C REGISTER ENABLE LOW LEVEL ON GTC001* BRANCH TO MAJOR 46 MINOR 61 ON NO-GO BRANCH TO MAJOR 46 MINOR 65	
6 61		FAULT IN RESET OF KKBO22 FF Load discrete input word (Eip/EOP Code) with a Enable vertical parity check Stop tape, display c register, no-go light on	
		I <u>INDICATORS I DISPLAY I REPLACE ASSEMBLIES</u> NO GO I <u>300 1A1A3A12</u> I <u>I2A1A2A(16+20)</u>	   AEC317* SƏ1 
6 62		SPARE	
6 63 6 64		SPARE Spare	
6 65 1	T238	TEST EOP 0362 I/C CMPLT -> RESET TST2(SIM NO-G0), INL TEST CLK STP WITH QUT029(ASG25)=1	
6 66		INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF4FFF ENABLE CONTINUOUS HIGH LEVEL ON GTCOOl*	SIM NO-GO
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3CA40 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3CA40 BRANCH TO MAJOR 46 MINOR 67 ON NO-GO	EA=0362, QUT029=0 I/O REQ

TESTICEC	ISION   TEST/FAULT EVELNUMBER	SELF-TEST PROGRAM	I REMARKS
6672	2 F238.N	FAULT EOP 0362 DECODE -> SHORT I/O CMPLT LOAD DISCRETE IMPUT WORD (EIP/EOP CODE) WITH A ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON INDICATORS I DISPLAY I BEPLACE ASSEMBLIES	1
		IND_GOIBLANKI2A1A2A(1+12+14)	CED262* \$@1
6 68		SPARE	
6 69 6 70		SPARE SPARE	
671 1	T239	TEST FOR NO RESET OF GTC001* TO 0	
46 72		READ & COMPARE MISCELLANEOUS WORD 1 WITH A00000C LOGICALLY 'AND' C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS ENABLE LOW LEVEL ON GTCOO1* BRANCH TO MAJOR 46 MINOR 73 ON ND-GO BRANCH TO MAJOR 46 MINOR 77	
¥6732	F239•N	FAULT IN INHIBIT STP CLK WITH QUT029 = 0 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		I INDICATORS I DISPLAY I REPLACE ASSEMBLIES	QUT029
6 74		SPARE	
6 75 6 76		SPARE SPARE	
677 1 678	T240	TEST EOP 0362 RESET OF GTC001* TO 0, QUT029 = 1 ENABLE CONTINUOUS HIGH LEVEL ON GTC001* LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3CA00 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3CA00 READ & COMPARE MISCELLANEOUS WORD 1 WITH A LOGICALLY 'AND' C REGISTER AND A00000C - RESULT IN B & C REGISTER BRANCH TO MAJOR 46 MINOR 79 ON NO-GO BRANCH TO MAJOR 46 MINOR 83	EA=0362, QUT029 = 1 I/O REQ
+6 79 Z	T240.N	FAULT IN EOP 0362 -> RESET KKB022 FF ENABLE LOW LEVEL ON GTC001* LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	

TESTIDECISI	ON   TEST/FAUL	T   SELF-TEST PROGRAM	I REMARKS
		IINDICATORSI_DISPLAYL	_ _  _  AEI030* S@1
5 80 5 81 5 82		SPARE Spare Spare	
5831 584	T241	TEST EOP 0370 I/O CMPLT -> RESET TST2(SIM NO-GO) INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF4FFF LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3E000 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3E000 BRANCH TO MAJOR 46 MINOR 85 ON NO-GO BRANCH TO MAJOR 46 MINOR 98	SIM NO-GO EA=0370 I/O REQ
5851	F241.N	FAULT IN EOP 0370 DECODE -> SHORT I/O CMPLT LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I	_  _  _  CED270≄ Sal
b     86       b     87       b     88       b     89       b     90       b     91       b     92       b     93       b     94       b     96       b     96       b     97		SPARE SPARE SPARE SPARE SPARE SPARE SPARE SPARE SPARE SPARE SPARE SPARE SPARE	
5 98 5 99		ENABLE VERTICAL PARITY CHECK END OF MAJOR TEST	

TESTICECIS	ION   TEST/FAULT   EL 1NUMBER1	SELF-TEST PROGRAM	1 REMARKS 1
	* * *	THIS MAJOR NUMBER ALSO USED FOR TEST/FAULT LOC AFTER MAJOR 99	*
47 00 47 01 47 02 47 03		BRANCH TO MAJOR 47 MINOR 3 Stop Tape, Display C register, NO-go light on Stop Tape, Display C register, NO-go light on END of Major Test	

ITESTICE		TEST/FAULT	SELF-TEST PROGRAM	R EM ARK S
48 00	2	F242.2	BBC133* SaO	
			I INDICATORS I DISPLAY I BEPLACE ASSEMBLIES I ISSUE INCLASSEMBLIES	
			PUNCH TAPE LEADER 12 INCHES LONG Branch to Major 48 minor 3	
48 01 48 02			STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
48 03	1	T242	TEST 258 OF MABC Branch to Major 49 Minor 2	
48 04			END OF MAJOR TEST	

ITESTIDECISION   TEST/FAULT    _ND_1LEVEL1NUMBER1	SELF-TEST PROGRAM	REMARKS
		I

49 00	BRANCH TO MAJOR 49 MINOR 3
49 01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
49 02	
49 03	END OF MAJOR TEST

	N   TEST/FAULT	I SELF-TEST PROGRAM	I REMARK S
	************	*****	*************
	* * *	TESTS OF MEMORY CONTROL - MAJORS 50 & 51 Test 7245 - 7280	* * *
	*********	***************************************	*****
0 00		INITIALIZE CEFINE SELF TEST TAPE SET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST NCU CLOCK MODE (GTCCO3*)	
		ENABLE LOW LEVEL ON GTC001* Branch to major 50 minor 3	
0 01		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
0 0 3 1	T245	TEST MFIL => RESET TST2(SIM NO-GO) ON CMA121	
0 04		PREVIOUS TEST = (48)T242 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFDF0F0FFF	MTW1 REC->[NMX ON CMA121 SIM CM7
		ENABLE LO SPEED MEMORY NODE WITH ADDRESS: O DATA: O Punch tape leader 12 Inches Long	
		BRANCH TO MAJOR 50 HINOR 5 ON NO-GO INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF4FFF RESET MEMORY FILL MODE	SIM NO-GO
		SERIALLY LOAD THE B REGISTER FROM THE A REGISTER PUNCH TAPE LEADER 12 INCHES LONG BRANCH TO MAJOR 50 MINOR 6 ON NO-GO BRANCH TO MAJOR 50 MINOR 8	
0 05 2	F245.1	FAULT IN MFIL IBT => CMA121 RESET MEMORY FILL MODE PUNCH TAPE LEADER 12 INCHES LONG	
		ENABLE VERTICAL PARITY CHECK Set the I/O complete flag (GtColo*) Reset the I/O complete flag (GtColo*) Stop tape, Display C register, NO-go light on	RESET TST2

TESTICECISI	DN   TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
		I <u>INDICATORS I DISPLAY I</u> REPLACE ASSEMBLIES NO GO I BLANK IIAIA2AI5 I IIAIA3A(1+7+26)	
0062	F245.2	FAULT IN INH OF HMFL SET THE I/O COMPLETE FLAG (GTCO10*) RESET THE I/O COMPLETE FLAG (GTCO10*) STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	RESET TST2
		INDICATORS I DISPLAY I BEPLACE ASSEMBLIES INO GO ( BLANK  1A1A1A(10,18)	
0 07		SPARE	
0 08 1 0 09	T246	TEST FOR MFIL FF RESET INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFOF4FFF BRANCH TO MAJOR 50 MINOR 13 ON NO-GO PUNCH TAPE LEACER 12 INCHES LONG	RESET TST2 ON CMA121, SIM ND-GO ND-GO = PASS
0102	F246.G	MFIL NOT RESET ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON COMPARE THE B REGISTER TO O	SET UP AREG SAT FAULT TO Stop tape
		IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES IND_GOIBLANKIIAIA2AI5 ITEST_SET_FAULT_I400011AIA3A01	   AAD101* SƏ1   KMA111* SƏ0
0 11 0 12		SPARE SPARE	
0131	T247	TEST FOR SIGNALS PRESET DURING MFIL CMA121, CFLG* DR -> MTW1 REC ON CMA121 IN T246 SIGNAL ROUTING: GTC002* -> QUT007 GTC0021* -> QUT0016 GTC002* -> QUT017	
0 14		GTHOOI* -> QUTOIN GTHOOI* -> QUTOIN COMPARE THE B REGISTER TO A LOGICALLY "AND" C REGISTER AND A0201C - RESULT IN B & C REGISTER BRANCH TO MAJOR 50 MINOR 15 ON NO-GO BRANCH TO MAJOR 50 MINOR 18	

TESTIDEC		TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
50 15 2	2	F247.N	FAULT IN SIGNALS PRESENT DURING MFIL CMA121 Enable vertical parity check Stop tape, display c register, no-go light on	
			I INDICATORS 1 DI SPLAY I REPLACE ASSEMBLIES	   AMA115* SƏ1
			ILALA3A02 INO GO ( 10000 1A1A2A10 	I MA155* S@1
			OR      1A1A3A(4.5)  NO GO   4000 1A1A2A(10,20)	     BMA174* S@1
			I IIAIA3A(1.3) INO GO I 2000 1A1A3A02	GTW001* S@1
50 16 50 17			SPARE SPARE	
50 18 1 50 19	L	T248	TEST FOR NO RESET OF KMAO81 OR KMVO11 FFS ENABLE CONTINUOUS HIGH LEVEL ON GTCOO1* READ & COMPARE MISCELLANEOUS WORD 1 WITH AFEFFFC LOGICALLY 'AND' C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS ENABLE LOW LEVEL ON GTCOO1* BRANCH TO MAJOR 50 MINOR 20 ON NO-GO BRANCH TO MAJOR 50 MINOR 23	
50202	2	F248.N	FAULT IN RESET OF KMA081 OR KMV011 FFS         ENABLE VERTICAL PARITY CHECK         STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON         I       INDICATOBS         I       DISPLAY         I       REPLACE ASSEMBLIES         IND.GO       I         20030011A1A3A(1, 21)         IND.GO       I         I       20000011A1A3A(1, 21)	   AKB111# SƏ1   AMA028# SƏ1   KMA091 SƏ1
			IND_GD     I     20000118183806       IND_GD     I     40300118183806       IND_GO     I     300118183801	KMAO91 SƏ1   KMAO81 SƏ1
50 21 50 22			SPARE SPARE	
50231 5024	L	T249	TEST INHIBIT OF SHORT DATA TO AREG DURING MFIL SERIALLY LOAD THE 8 REGISTER WITH AFFFFFF Compare the 8 register to the A register Reset memory fill mode Branch to major 50 minor 25 on ND-go Branch to major 50 minor 28	

	LEVEL	I TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
0 25	2	F249.N	FAULT IN IMA124* ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDIGATORSI_DISPLAYI	{
0 26 0 27			SPARE SPARE	
0 28 0 29	1	¥250	TEST FOR "CLEAR MB" PULSE DURING MFIL, GTB000* -> QUT006 ON BMA165 SERIALLY LOAD THE B REGISTER WITH AFFFFFF INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF1F1F0FFF ENABLE LO SPEED MEMORY MODE WITH ADDRESS: O DATA: O RESET MEMORY FILL MODE COMPARE THE B REGISTER TO A LOGICALLY 'AND' C REGISTER AND A04 - RESULT IN B & C REGISTER BRANCH TO MAJOR 50 MINOR 30 ON NO-GO BRANCH TO MAJOR 50 MINOR 37	MTW1 REC -> INMX ON BMAI65
io 30	2	T250.N	TEST CFLG* DR -> MTW1 REC ON KMA091	
50 31			SIGNAL ROUTING: GTC013* -> QUT012 GTC020* -> QUT014 SERIALLY LOAD THE B REGISTER WITH AFFFFFF INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF1F080FFF PUNCH TAPE CODES - /0 /4 #0 &C #0 &C #0 &C #0 &C RESET MEMORY FILL MODE COMPARE THE B REGISTER TO A LOGICALLY 'AND' C REGISTER AND A0014 - RESULT IN B & C REGISTER BRANCH TO MAJOR 50 MINOR 32 ON NO-GO	MTW1 REC -> INMX DN KMA091 MFIL (ADDR=0 DATA=0,0,0)
	2	F 2 50• NG	FAULT IN "CLEAR MB" Enable vertical parity check Stop tape, display c register, no-go light on	
			I_INDICATORSI_DISPLAYIREPLACE_ASSEMBLIES IND_GOI_BLANKI1A1A2A10 II_IA1A3A12.3.19.201	   BMA165* SƏ1 
50 32 50 33	3	T250 <b>.</b> NN	TEST LOAD CM8 ON KMAOGI INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF3F2F4FFF ENABLE LO SPEEC MEMORY MODE WITH ADDRESS: O DATA: O RESET MEMORY FILL MODE BRANCH TO MAJOR 50 MINOR 34 ON NO-GO	RESET SIM NO-GO ON KMAO61

	LEVEL	I TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
	4	F250.NNG	FAULT IN NYKO12* -> RESET TST2 OR KMAO71 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
			I <u>INDICATORS</u> I <u>DISPLAY</u> I <u>REPLACE ASSEMBLIES</u> INO GO I BLANK IIAIA3A(1,20) II2AIA3AI5	- -! -! -!
0 34	4	F2 50. NNN	FAULT IN INITIALIZE SEQUENCE ENABLE VERTICAL PARITY CHECK SET THE I/O COMPLETE FLAG (GTCO10*) Reset The I/O complete flag (GTCO10*) STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	RESET TST2
			INDICATORS I DISPLAY I REPLACE ASSEMBLIES	
035 036			SPARE SPARE	
0 37	1	T251	TEST CFLG* DR -> MTW1 REC ON KMA091	
038			SIGNAL ROUTING: GTC013* -> QUT012 GTC020* -> QUT014 SERIALLY LOAD THE B REGISTER WITH AFFFFFFF INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF1F0B0FFF PUNCH TAPE CODES - /0 /4 #0 &C #0 &C #0 &C RESET MEMORY FILL MODE COMPARE THE B REGISTER TO A00000C LUGICALLY 'AND' C REGISTER AND A00140C - RESULT IN B & C REGISTER	MTW1 REC -> INMX ON KMAO9 MFIL (ADDR=0 DATA=0,0,0)
	2	F251.1	FAULT LOC WITHIN TEST T251 - BREG SATURATED DURING VERIFY COMPARE	- - -1 -1
	1	T251(CONT)	ENABLE LOW LEVEL ON GTCOO1* Branch to major 50 minor 39 on No-Go Branch to major 50 minor 44	
0 39	2	T251.2	REPEAT TEST T251 EXCEPT ON KMVOLL	
0 40			SIGNAL ROUTING: GTC013* -> QUT012 GTC020* -> QUT014 SERIALLY LOAD THE B REGISTER WITH AFFFFFFF INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF1F070FFF PUNCH TAPE CODES - /0 /4 #0 &C #0 &C #0 &C #0 &C	MTWI REC -> INMX ON KMVO11 MFIL (ADDR=0 DATA=0,0,0)

	ECISION	TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
			COMPARE THE B REGISTER TO A00000C Logically 'And' C register and a00140C - result in B & C register Branch to major 50 minor 41 on NO-GO Enable low level on gtco01*	
	3	F251.2.G	KMA091 OR KYRO21* SƏO Enable Vertical Parity Check STOP Tape, Display C Register, NO-GO Light on	
			I INDICATORS I DISPLAY I REPLACE ASSEMBLIES	1
0 41	3	F251.2.N	FAULT IN LOAD MB CONTROL ENABLE VERTICAL PARITY CHECK SET THE I/O COMPLETE FLAG (GTCO10*) RESET THE I/O COMPLETE FLAG (GTCO10*) ENABLE LOW LEVEL ON GTCOO1* STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	RESET TST2
			IINDICATORSI_DISPLAYREPLACE_ASSEMBLIES         IND_GDI_24030011A1A3A11+2.3.6)         IND_GDI       20000011A1A3A(2.9)         INO_GOI       20000011A1A3A(2.9)         INO_GOI       40000(1A1A2A11)         IIA1A3A06       IA1A3A06         INO_GOI       30011A1A3A(3.7)	   MMA036* SƏ1 OR KMV011 SƏ(   GTC013* SƏ1   KMV011* SƏ1       (MA055* SƏ1
0 42 0 43			SPARE SPARE	1 INAUJJ 301
0 44 ) 45	1	T252	TEST REPETATIVE LOAD MB WITH DATA, AREG->MBDR->JEBREC->INMX->BREG ON KMA091 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH 0B3F0B0FFF PUNCH TAPE CODES - /0 /4 #0 &C #0 &C #0 &C #0 &C #F #F #F #F #F	JEB->INMX ON KMA091
			#F #A &C         RESET MEMORY FILL MODE         COMPARE THE B REGISTER TO AFFFFFF         BRANCH TO MAJOR 50 MINOR 46 ON NO-GO         BRANCH TO MAJOR 50 MINOR 49	MFIL (ADDR=0 DATA=0,0,0,AFFFFFF)
0 46	2	F252.N	AMA053* SƏ1 Enable vertical parity Check Stop Tape, Display C Register, NO-go light on	

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TESTICECISION	TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
		II_DISPLAY	-   
50 47 50 48		SPARE	
50 49 1	T2 53	TEST CLEAR CM & CP. CFLG* DR -> MTW1 REC ON KMA051	
50 50		SIGNAL ROUTING: GTM010* -> QUT005 GTP000* -> QUT004 INITIATE SELF TEST MCDE 2-LOAD SELF TEST REGISTER WITH OF1F4F0FFF ENABLE LO SPEED MEMORY MODE WITH ADDRESS: 0 DATA: 0 RESET MEMORY FILL MODE COMPARE THE B REGISTER TO A LOGICALLY 'AND' C REGISTER AND A18 - RESULT IN B & C REGISTER BRANCH TO MAJOR 50 MINOR 51 ON NO-GO BRANCH TO MAJOR 50 MINOR 54	MTW1->INMX ON KMAO51
50 51 2	F253.N	FAULT IN CLEAR CM & CP ENABLE VERTICAL PARITY CHECK SET THE I/O COMPLETE FLAG (GTCO10*) RESET THE I/O COMPLETE FLAG (GTCO10*) STOP TAPE, DISPLAY C REGISTER, NO-GQ LIGHT ON	RESET TST2
		INDICATORS         I DISPLAY         REPLACE ASSEMBLIES           IND GD         I 10000000011A1A2A19           IND GD         I 140000000[1A1A3A20           IND GD         I 140000000[1A1A3A20	-    CTM110 S@0   KMA051* S@1 
		iiiiiiii	_! _  CTP100 S@0
50 52 50 53		S <sup>d</sup> are Spare	
50 54 1 50 55	Τ254	TEST LOAD CM8 ON KMA061, CM* DR -> JCM* REC SERIALLY LOAC THE 8 REGISTER WITH AFFFFFF INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF2F2F0FFF ENABLE LO SPEED MEMORY MODE WITH ADDRESS: O DATA: O RESET MEMORY FILL MODE COMPARE THE B REGISTER TO A808 BRANCH TO MAJOR 50 MINOR 56 ON NO-GO BRANCH TO MAJOR 50 MINOR 59	JCM*->INMX ON KMAO61

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	ECISION	1 TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
0 56	2	F254•N	FAULT IN LOAD CM8 DURING MFIL ENABLE VERTICAL PARITY CHECK Set the I/O complete flag (gtco10*) Reset the I/O complete flag (gtco10*) Stop Tape, display c register, NO-GO light on	RESET TST2
			INDICATORSDISPLAYBEPLACE_ASSEMBLIES NO_GOI 100000000011A1A2A07 NO_GOI 100200000011A1A3A20 II 0R IIA1A3A01 NO_GOI 200000011A1A2A07	   ATM404 S@0   KMA061* S@1       ATM403 S@0
				A10403 300
0 57 0 58			SPARE SPARE	
0 59 0 60	2	T255	TEST LOAD CP, AREG -> CP* DR -> NAD* REC -> BREG ON KMAO61 INITIATE SELF TEST MCDE 2-LOAD SELF TEST REGISTER WITH 073F2F0FFF ENABLE LO SPEED MEMORY MODE WITH ADDRESS: AFFFE DATA: O RESET MEMORY FILL MODE	NAD*~>INMX ON KMA061
			COMPARE THE B REGISTER TO AFFFE Branch to major 50 minor 61 on NO-Go Branch to major 50 minor 64	
0 61	2	F255.N	FAULT IN MFIL => EN CP* DR ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	1
				CPT203 INACTIVE
0 62 0 63			SPARE SPARE	
i0 64	1	T256	TEST CFLG* DR -> MTW1 ON KMV011	
0 65			SIGNAL ROUTING: GTC020* -> QUT014 GT1000* -> QUT003 GTE000* -> QUT002 GTA000* -> QUT001 SERIALLY LOAD THE B REGISTER WITH AFFFFFFF INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF1F070FFF ENABLE LO SPEED MEMORY MODE WITH ADDRESS: 0 DATA:	MTW1->INMX ON KMVOI1
			O RESET MEMORY FILL MODE	

NO.1_LEVEL	I TEST/FAULT <u>NUMBER</u>	I SELF-TEST PROGRAM	1 REMARKS
		LOGICALLY 'AND' C REGISTER AND AEOO4 - RESULT IN B & C REGISTER Branch to Major 50 minor 66 on NO-GO Branch to Major 50 minor 69	
0662	F256.N	FAULT IN SIGNALS DURING KMVO11 ENABLE VERTICAL PARITY CHECK SET THE I/O COMPLETE FLAG (GTCO10*) RESET THE I/O COMPLETE FLAG (GTCO10*) STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IIDICATORSIDISPLAYREPLACE ASSEMBLIES [ND_GDI_160004000011A1A3A20	RESET TST2 KMV011
		NO_GO1_16000000011A1A2A06	INPUT TO OTW150 OPEN
0 67 0 68		SPARE SPARE	
50 69 1 50 70	T257	TEST LOAD MB DURING HMFL AND SPEED CHANGE INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OB3F0B0FFF PUNCH TAPE CODES - /8 /4 PUNCH TAPE LEADE® 12 INCHES LONG PUNCH TAPE CODES - #0 &C #0 &C #0 &C #F #F #F #F #F #F #F #A &C	JEB->INMX ON KMAO91 HMFL (ADDR=0
		COMPARE THE B REGISTER TO AFFFFFF Branch to major 50 minor 71 on ND-GO Branch to major 50 minor 74	DATA=0,0,0,AFFFFFF)
50712	F257.N	FAULT IN HMFL ENABLE VERTICAL PARITY CHECK SET THE I/O COMPLETE FLAG (GTCO10*) Reset The I/O complete flag (GTCO10*) Reset memory fill mode Punch Tape Leader 12 inches Long Stop Tape, Display C Register, NO-GO Light ON	RESET TST2
		INDIGATORS I DISPLAY I REPLACE ASSEMBLIES	   AAD101* SƏ1 
i0 72 i0 73		SP AR E SP AR E	
074 L	T 258	TEST SPEED CHANGE DURING HMFL Reset memory fill mode Stop tape, display c register, ND-GQ light on	

	DECISION	TEST/FAULT	I SELF-TEST PROGRAM	R EMARK S
			INDICATORS   DISPLAY   <u>REPLACE ASSEMBLIES</u> NO GO  XXXXXXXXX 1A1A1A(10,16,18)     1A1A3A(1,8,14)         OR           OR	- 1 - 1 - 1 - 1 - 1 - 1
	1	T258(CONT)	PUNCH TAPE LEADER 12 INCHES LONG Branch to major 50 minor 76	
50 75			SPARE	
50 76 1 50 77	T259	TEST DECODE OF CM1, AREG=CM1->CM+DR->JCM+REC->CM1 DECODE->GREG->DSPL->INMX->RIM ->BREG INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFB7DFOFFF	GREG->DSPL, DSPL->INMX, Inmx->breg on Ktl501	
		PULSE THE CM DRIVERS WITH 03 Compare the B register to A4 Logically *And* C register and A register-result in B & C registers Branch to major 50 minor 78 on NO-go Branch to major 50 minor 84	DATA = CM1	
50 78 50 79	2	T 2 59. N	TEST DECODE OF CP1023 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFB7DF0FFF PULSE THE MB DRIVERS WITH O7FE COMPARE THE B RÉGISTER TO AB LOGICALLY 'AND' C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS BRANCH TO MAJOR 50 MINOR 80 ON NO-GO	GREG->DSPL, DSPL->INMX, INMX->BREG ON KTL501 DATA = CP1023 CODE
	3	F259.NG	FAULT IN CM1 DECODE -> GREG STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIES IND_GOIBLANKI1A1A3A18	       KD041
50 80	3	F259.NN	FAULT IN EN GREG -> DSPL STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES IND_GOI_10000000011A1A3A121.26)	     gvm137 Səo
50 81 50 82 50 83			SPARE SPARE SPARE	

TESTICE	CISION   TEST/FAUL Level   NUMBER	T   SELF-TEST PROGRAM	REMARKS
084 085	1 T260	TEST DECODE OF CM7, AREG=CM7->CM*DR->JCM*REC->GREG->DSPL->INMX->BREG SERIALLY LOAD THE B REGISTER WITH AF INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFB7DFOFFF PULSE THE CM DRIVERS WITH C COMPARE THE B REGISTER TO A LOGICALLY "AND" C REGISTER AND A2 - RESULT IN B & C REGISTER BRANCH TO MAJOR 50 MINOR 86 ON NO-GO BRANCH TO MAJOR 50 MINOR 89	GREG->DSPL; DSPL->INMX; INMX->BREG ON KTL501 DATA = CM7 CODE
086	2 F260•N	FAULT IN CM7 DECCDE STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I <u>INDICATORS</u> I <u>DISPLAY</u> I <u>REPLACE ASSEMBLIES</u> NO GO I 20000000011A1A3A18 I <u>IA1A4A112,20</u>	-   AMD031* 501 
087 088		SPARE	
0 89 0 90	1 T261	TEST DECODE OF CP1023 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFB7DFOFFF PULSE THE MB DRIVERS WITH O7FE COMPARE THE B REGISTER TO A8 LOGICALLY "AND" C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS BRANCH TO MAJOR 50 MINOR 91 ON NO-GO BRANCH TO MAJOR 50 MINOR 93	GREG->DSPL, DSPL->INMX, INMX->BREG ON KTL501 DATA = CP1023 CDDE
0 91	2 F261•N	FAULT IN DECODE OF CP1023 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES INO GOI 1000000000(1A1A3A18 II_1A1A4A(16,20)	   IMD042 Sa0 
50 92		SPARE	
50 93 50 94	1 T262	TEST FOR CM1 CM7 & CP1023 DECODES INACTIVE INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFB7DF0FFF Compare the & register to A2 Logically "And" c register and AE - result in B & c register Branch to major 50 minor 95 on NO-GO Branch to major 50 minor 98	GREG->DSPL, DSPL->INMX
50 95	2 F262	CM1 CM7 OR CP1023 DECODE ACTIVE Stop tape, display c register, no-go light on	

سی چرین کی شرح بادی اسی میں میں چرین کا نے میں این میں ایک میں کر اور اور اور اور اور اور اور اور اور او	وا الا الله الم المانية المانية المانية المانية المانية المانية المانية المراجع المانية المانية المانية المانية المانية المانية المانية المانية المانية المانية المانية المانية المانية المانية المانية المانية المانية المانية المانية المانية المانية المانية المانية المانية المانية المانية المانية المانية المانية المانية المانية المانية المانية المانية المانية المانية المانية المانية المانية ال	ید میچ ود وی وی ان افغان اید به محمد میدون شنود و پاک کری از افغان افغان از میچ و ا
TESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	REMARKS 1
1 NO.1 LEVEL I NUMBER I		1
······································		

INDICATORS	I DI SPLAY I BEPLACE ASSEMBLIES	
IND GO	1 10000000001A1A3A18	1 IND042 \$21
	<u> </u>	1
NO GO	400000000114143418	IKD041 Sal
1	1I1A1A4A(12,20)	1
INO GO	20000000114143418	AMD031 520
1	1I1A1A4A(12,20)	

50 96	SPARE
50 97	SPARE

50 98 ENABLE VERTICAL PARITY CHECK

50 99 END OF MAJOR TEST

TESTIDECISI	ION   TEST/FAULT ELNUMBER	I SELF-TEST PROGRAM	I REMARKS
51 00		INITIALIZE DEFINE SELF TEST TAPE SET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST NCU CLOCK MODE (GTC003*) ENABLE LOW LEVEL ON GTC001* BRANCH TO MAJOR 51 MINOR 3	
51 01 51 02		STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
51 03 1 51 04	7263	TEST FOR LVWC SELF TEST CYCLE HANGUP, EN MB -> STE INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH 8F3F0F0FFF	INH ALL MEM LD, MEM EN MB->STE
		ENABLE WORST CASE MEMORY MODE-ADDRESS: O PATTERN: O	
2	F263.1	LVWC SELF TEST CYCLE HANGUP	
		I INDICATORS I DI SPLAY I REPLACE ASSEMBLIES	
1	T263(CONT)	BRANCH TO MAJOR 51 MINOR 7	
51 05 51 06		SPARE SPARE	
51 07 1 51 08	T264	TEST FOR RESET OF ALL MEMORY EN LD BREG SIGNALS SERIALLY LOAD THE B REGISTER WITH A INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF9FF10FFF	MTW1->INMX ON ANY MEMORY LU Breg Signal
		COMPARE THE B REGISTER TO A Branch to major 51 minor 9 on NO-Go Branch to major 51 minor 12	
51092	F264•N	FAULT IN RESET OF MEM LD BREG SIGNALS ENABLE VERTICAL PARITY CHECK SET THE I/D COMPLETE FLAG (GTCO10*) RESET THE I/D COMPLETE FLAG (GTCO10*) STOP TAPE, DISPLAY C REGISTER, NO-GD LIGHT DN	RESET TST2
		IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESIND_GOIXXXXXXXXXIIAIA3A(1+4+231	IMVO61 OR KMA152
51 10 51 11		SPARE SPARE	
51 12 1	T265	TEST FOR RESET OF TST2(SIM NO-GO) ON CMA121 DURING LVWC, CFLG+->MTW1	

• • • •		I TEST/FAULT	I SELF-TEST PROGRAM	REMARKS
51 13			INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF9F0F4FFF ENABLE WORST CASE MEMORY MODE-ADDRESS: 0 PATTERN: 0	MTW1->INMX, RESET SIM NC-GO ON CMA121
	2	F265.1	FAULT LOC WITHIN T265 - LVWC SELF TEST CYCLE, WITH NO TST2 CONTROL, Hangup	
			IINDICATORS I DISPLAY IREPLACE_ASSEMBLIES	   AMV174* 501
	1	T265(CONT)	BRANCH TO MAJOR 51 MINOR 14 ON NO-GO Branch to Major 51 minor 18	
51 14	2	F265.N	FAULT IN LVWC IBT OR FF ENABLE VERTICAL PARITY CHECK SET THE I/O COMPLETE FLAG (GTCO10*) RESET THE I/O COMPLETE FLAG (GTCO10*) STOP TAPE, DISPLAY C REGISTER, NO⊸GO LIGHT ON	RESET TST2
			I <u>INDICATORS</u> I <u>DISPLAY</u> I <u>BEPLACEASSEMBLIES</u> INO GOI BLANK IIAIAZAIS IIAIA <u>3A(1+7+8)</u>	
51 15 51 16 51 17			SPARE SPARE SPARE	
51 18 51 19	1	T266	TEST FOR RESET OF "MEMORY VERIFY MODE" COMPARE THE B REGISTER TO A LOGICALLY "AND" C REGISTER AND A0001 - RESULT IN B & C REGISTER BRANCH TO MAJOR 51 MINOR 20 ON NO-GO BRANCH TO MAJOR 51 MINOR 23	
51 20	2	F266.N	NO RESET OF MEMORY VERIFY MODE ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I INDICATORS I DISPLAY I BEPLACE ASSEMBLIES ING GO I 1000011A1A3A(1,4)	 I I CMB074 SƏ1
51 21 51 22			SPARE SPARE	
51 23 51 24	1	T267	TEST "WORST CASE LOAD STROBE" => GTB000* -> QUT006 QN CMV053* INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF1F1F0FFF ENABLE WORST CASE MEMORY MODE-ADDRESS: O PATTERN: O COMPARE THE B REGISTER TO A LOGICALLY 'AND' C REGISTER AND A0401 - RESULT IN B & C REGISTER	MTW1->INMX ON CMV053+

	ECISION	I TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
			BRANCH TO MAJOR 51 MINOR 25 ON NO-GO Branch to Major 51 minor 29	
51 25	2	F267.N	FAULT IN CMV053* => LD BREG ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYI	CMV053*
51 26 51 27 51 28			SPARE SPARE SPARE	
51 29 51 30	1	T268	TEST SHIFT OF AREG ONCE DURING LOAD PORTION OF LVWC S.T. CYCLE SERIALLY LOAD THE B REGISTER WITH A INITIATE SELF TEST MODE 2→LOAD SELF TEST REGISTER WITH OB3FOBOFFF ENABLE WORST CASE MEMORY MODE-ADDRESS: O PATTERN: AFFFFFFF COMPARE THE B REGISTER TO D7FFFFFF BRANCH TO MAJOR 51 MINOR 31 ON NO-GO BRANCH TO MAJOR 51 MINOR 34	JEB->INMX ON KM4091
51 31	2	F268.N	FAULT IN SHIFT AREG DURING LOAD PORTION OF LVWC         ENABLE VERTICAL PARITY CHECK         STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON         Indicators         Indicators	I I INPUT TO AMCO22 OR IMB135
			I 2AIAIA04 INO GO I 70000000011AIA3A05 I 2AIA2A19	IMB135* S@1
51 32 51 33			SPARE SPARE	
51 34 51 35	1	T269	TEST GTC020+ -> QUT014 ON KMV011 DURING LVWC, TEST FOR 2 SHIFTS OF AREG INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF1F070FFF ENABLE WORST CASE MEMORY MODE-ADDRESS: O PATTERN: 80000002 COMPARE THE B REGISTER TO A LOGICALLY 'AND' C REGISTER AND A0004 - RESULT IN B & C REGISTER BRANCH TO MAJOR 51 MINOR 36 ON NO-GO BRANCH TO MAJOR 51 MINOR 40	MTW1->INMX ON KMVOll
51 36	2	F269.N	FAULT IN VERIFY PORTION OF LVWC, SHIFT OF AREG ENABLE VERTICAL PARITY CHECK	

TESTICECISI	ON   TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
		II DISPLAY	   BMA162* SƏ1   KMA152
51 37 51 38		SPARE SPARE	
51 39		SPARE	
51 40 1	T270	TEST COMPLETE LVWC S.T. CYCLE, CREG->ROM->WD1*DR->NAD*REC->BREG 3 TIMES, 3COMPARES- 2NO-GO THEN GO	
51 41		SERIALLY LOAD THE B REGISTER WITH A5555555	
		COMPARE THE B REGISTER TO A Initiate Self test mode 2-load self test register with 8F3F0F08FF	CREG = OAAAAAAA CREG->ROM, ROM->WD1+DR/MB->STE, INH ALL MEM LD BREG
		ENABLE WORST CASE MEMORY MODE-ADDRESS: O PATTERN: 2AAAAAAA Set the I/O complete flag (gtcolo*) Reset the I/O complete flag (gtcolo*) Branch to major 51 minor 43 on NO-GO	RESET TST2
51 42 2	F270.N	FAULT IN ENABLE OF VERIFY FUNCTION Enable vertical parity check Stop tape, display c register, no-go light on	
		I INDICATORS I DISPLAY I REPLACE ASSEMBLIES	CARO19 DR AYR200
5143 1	1271	TEST COMPLETE LYNC S.T. CYCLE, CLEAR NO-GO FROM T269,	
51 44		AREG->ROM->WD1*DR->NAD*REC->BREG 3 TIMES GO INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH 8F3F0F0FFF	EN MEM MB->STE, INH ALL MEM LD BREG
		ENABLE WORST CASE MEMORY MODE-ADDRESS: 00000 PATTERN: AAAAAAAA Set the I/O Complete Flag (GTC010*) Reset the I/O Complete Flag (GTC010*) Branch to Major 51 Minor 45 on NO-GO Branch to Major 51 Minor 49	RESET TST2
51 45 2	F271.N	FAULT IN RESET OF NO-GO, OR VERIFY MÁLFUNCTION Enable vertical parity check Stop Tape, display c register, no-go light on	

TESTIDECISION	I TEST/FAULT	I SELF-TEST PROGRAM	REMARKS
		INDICATORS I DISPLAY I REPLACE ASSEMBLIES NO GO XXXXXXXXXXIIAIA3A(8,17,23) I IIAIA4A16 I IZAIAIA02	 
51 46 51 47 51 48		SPARE SPARE SPARE	
51 49 1 51 50	T272	TEST EN MB->NAD PULSE, XTD104*->QUT021 (MTW2) ON IMV061 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH 8F3F0D0FEF	EN MEM MB->STE, MTW2->RIM O
		ENABLE WORST CASE MEMORY MODE-ADDRESS: 0 PATTERN: 00000001 Logically 'And' c register and A00008 - result in B & C register Branch to major 51 minor 51 on NO-GO Branch to major 51 minor 54	IMVO61 CHECK QUTO21 DURING VERIFY MASK FOR QUTO21
51 51 2	F272.N	FAULT IN ANV161* => XTD104* ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I	 1 1
51 52 51 53		SPARE SPARE	
51 54 1 51 55	T273	TEST SMFA => GTC021* = 0 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF9F0F0FFF ENABLE SINGLE MEMORY MODE WITH ADDRESS: 0 DATA: 0 COMPARE THE B REGISTER TO A LOGICALLY "AND" C REGISTER AND A0001 - RESULT IN B & C REGISTER BRANCH TO MAJOR 51 MINOR 56 ON NO-GO BRANCH TO MAJOR 51 MINOR 60	MTW1->INMX ON CMA121
51 56 2	F273.N	INPUT TO CMA145 OPEN Enable vertical parity check Stop Tape, display c register, ND-G0 light on	

TESTIDECISION	I TEST/FAULT	I SELF-TEST PROGRAM	REMARKS
		INDICATORS I DISPLAY I BEPLACE ASSEMBLIES	
51 57		SPARE	
51 <b>58</b> 51 <b>59</b>		SPARE SPARE	
51 60 1 51 61	T2 74	TEST FOR NO SET OF SINGLE LOAD MEMORY FF WITH CM7 PRESENT & SLMC SERIALLY LOAD THE B REGISTER WITH A62FFFFF INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFDF0F0FFF PULSE THE CP DRIVERS WITH 0; MB DRIVERS WITH THE C REGISTER COMPARE THE B REGISTER TO A62FFFFF BRANCH TO MAJOR 51 MINOR 62 DN NO-GO BRANCH TO MAJOR 51 MINOR 65	SIM CM7, O->BREG ON CMA121
51 62 2	F274.N	NO INH OF SLMC LATCH WITH CM7 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON I INDICATORS 1 DISPLAY 1 REPLACE ASSEMBLIES IND GD 1.1777777711A1A3A(1.2.8)	   AMA129# SƏ1
51 63 51 64		SPARE SPARE	
51 65 I 51 66	T275	TEST SET OF "SINGLE LOAD MEM FROM CREG" LATCH, CHECK AFFECT ON DATA IN Areg with compare Serially load the B register with A	
21 00		COMPARE THE B REGISTER TO AAAAAAAA Initiate self test mode 2-load self test register with ob3f070FFF Pulse the CP drivers with the A register & MB drivers with the C reg. Punch tape codes - &C	CREG = OAAAAAAA Jeb->Inmx on kmaoll
		COMPARE THE B REGISTER TO AOAAAAA Initiate self test mode 2-load self test register with of7fofofff	CM7 TO RESET SLMC LATCH, A Mem LD BREG INACTIVE
		LOGICALLY "AND" C REGISTER AND FFFFFFFF - RESULT IN B & C REGISTER Compare the B register to AGA Branch to Major 51 minor 67 on ND-go Branch to Major 51 minor 70	
51 67 2	F275.N	SLMC INT OR LATCH FAULT	

ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON

TESTIDECISION	TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
		I INDICATORS I DI SPLAY I REPLACE ASSEMBLIES	   AMA033* SƏ1 
51 68 51 69		SPARE SPARE	
51 70 1	T276	TEST ACTUAL DATA TRANSFER DURING SLMC+ SETS UP CM7 CODE WHICH RESETS AMA033, BREG + CREG -> ROM -> MB DR -> JEB REC + BIT 27(DIHR->MTW2) -> BREG ->	
51 71		ROM -> CM+DR -> JCM REC = CM7 Load discrete input word (Eip/Egp CGDE) with Abff7f Serially Load the B register with A000ffff	81 <b>1</b> 27 OF MTW2 = 1
		COMPARE THE B REGISTER TO ABO7AAAA Initiate self test mode 2-load self test register with 483f0707ef	CREG = 08075555, C+B REG = A807FFFF BREG->ROM, ROM->CM*DR, JEB->INMX, MTW2->RIM, ON KMV011
		PULSE THE CP DRIVERS WITH THE A REGISTER & MB DRIVERS WITH THE C REG. PUNCH TAPE CODES – &C	ON KMVOII ROM = ACO7FFFF -> CM+DR -> JCM+ = CM7 => RESET SLMC LATCH
		SET THE I/O COMPLETE FLAG (GTC010*) Reset the I/O complete flag (GTC010*) Branch to major 51 minor 76	RESET TST2 If Slmc Latch not reset go to min 80
51 72 51 73 51 74 51 75		SPARE SPARE SPARE SPARE	
51 76 1 51 77	T277	TEST FOR SREM RESET OF TST2 ON CMA121 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBF0F4FFF SINGLE READ MEMORY MODE-READ MB LINES-ADDRESS O BRANCH TO MAJOR 51 MINOR 78 ON NO-GO BRANCH TO MAJOR 51 MINOR 83	RESET SIM NO-GO ON CMA121
51 78 2	F277.N	FAULT IN SREM IBT OR FF => CMA121 ENABLE VERTICAL PARITY CHECK SET THE I/O COMPLETE FLAG (GTCO10*) RESET THE I/O COMPLETE FLAG (GTCO10*) STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	RESET TST2

المحاج والمحاجبة ويشد وجوي ويست ويوي ويون ويون ويواجه والمحاجب	- « الله الله الله الله الله الله الله ال	
TESTICECISION   TEST/FAULT	SELF-TEST PROGRAM	REMARKS
I_NO.I_LEVEL_I_NUMBERI		

I INDICATORS	1 DISPLAY	LBEPLACE_ASSEMBLIES	1
INO GO	I BLANK	11 A1 A2 A05 	KMA112* SƏ1

51 79 SPARE

51 80 2 F276.N FAULT IN SLMC INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF7F0F0FFF CM7

COMPARE THE B REGISTER TO ACO7FFFF

STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON

CM7 TO RESET SLMC LATCH, ALL MEM LD BREG INACTIVE CHECK FOR CORRECT CM7 CODE IN BREG

INDICATORS	I DISPLAY I REPLACE ASSEMBLIES	l I	
IND GO	[ 10000000011A1A3A22	AMA043*	=> CVM632
IND GO	140177777711A1A2A04	AMA054*	S@1
1	114143402		
NO GO	2540177777711A1A3A(13,22)	GVM551*	591
1	1201019		
IND GO	1BLANK11A1A3A08	AMD031*	INPUT TO CMA109 OPEN

51	81	SPARE
51	82	SPARE

51 83	1	T278	TEST FOR RESET OF KMAII2 Initiate self test mode 2-load self test register with ofbfff4fff	STM NO-GO
51 84			BRANCH TO MAJOR 51 MINOR 87 ON NO-GO	31H H0-90
51 85	2	F278.N	NO RESET OF KMA112 Enable vertical parity Check	
			SET THE I/O COMPLETE FLAG (GTCO10*)	RESET TST2
			RESET THE I/D COMPLETE FLAG (GTCO10*)	
			STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON	

I_INDICATORS	1_DI SPLAY	BEPLACE	ASSEMBLIESI	
INO_GO	BLANK	LIA1A3A(1+7)		

51 86 SPARE

51 87	1	Ť279	TEST FOR INH OF LOAD MB DURING SREM	
51 88			SERIALLY LOAD THE B REGISTER WITH A	
			INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF3FOBOF7F	ROM->RIM ON KMA091
			SINGLE READ MEMORY MODE-READ MB LINES-ADDRESS FFFFFF	
			COMPARE THE B REGISTER TO A	
			BRANCH TO MAJOR 51 MINOR 89 ON NO-GO	
			BRANCH TO MAJOR 51 MINOR 92	

TESTICECISIC	ON   TEST/FAULT LNUMBER	I SELF-TEST PROGRAM	I REMARKS
1892	F279	IMA132* SƏ1 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I	
1 90 1 91		SPARE SPARE	
51 92 1 51 93	T2 80	TEST FOR "INITIATE CI" DURING SREM ON IMVO61 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF1FODOFFF SINGLE READ MEMORY MODE-READ MB LINES-ADDRESS O COMPARE THE B REGISTER TO A LOGICALLY "AND" C REGISTER AND A0004 - RESULT IN B & C REGISTER BRANCH TO MAJOR 51 MINOR 94 ON NO-GO BRANCH TO MAJOR 51 MINOR 98	MTW1->INMX ON IMVO61
1942	F280.N	INPUT TO AMVO42 OR CHAO25 OPEN ENABLE VERTICAL PARITY CHECK SET THE I/O COMPLETE FLAG (GTCO10*) RESET THE I/O COMPLETE FLAG (GTCO10*) STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I	RESET TST2
1 95 51 96 51 97		SPARE SPARE SPARE	
51 98 51 99		ENABLE VERTICAL PARITY CHECK END OF MAJOR TEST	

TESTIDECISION   TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
52 00 52 01 52 02	BRANCH TO MAJOR 52 MINOR 3 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
52 03 1 T281	TEST LSB OF MABC Branch to major 44 minor 1	
52 04	END OF MAJOR TEST	

ITESTICECISION   TEST/FAULT	I SELF-TEST PROGRAM	REMARKS
53 00 53 01	BRANCH TO MAJOR 53 MINOR 3 STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON	
53 02 1 T283	TEST 3SB OF MABC Previous test = (44)t282 Branch to major 60 minor 2	
53 03	END OF MAJOR TEST	

ITESTIDECISION I TEST/F		SELF-TEST PROGRAM	<b>~</b> .	1 REMARKS
54 00	BRANCH TO MAJOR 54 MINOR	3		
54 OL 1 T331	TEST 5SB OF MABC Previous test = (75)T330 branch to major 79 minor	2		
54 02 54 03	STOP TAPE, DISPLAY C REGI End of Major Test	ISTER, NO-GO LIGHT ON		

TESTICECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS I
	SEET - TEST FROOKAM	I REARING I
INDAI LEVEL I NUMBER I		1

55 00	BRANCH TO MAJOR 55 MINOR 3
55 01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
55 02	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
55 03	END OF MAJOR TEST

ITESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS I
I_NO_I_LEVEL_I_NUMBERI		

56 00	BRANCH TO MAJOR 56 MINOR 3
56 01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
56 02	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
56 03	END OF MAJOR TEST

TESTICECISION   TEST/FAULT	SELF-TEST PROGRAM	REMARKS 1
	JEEL TEST FROORAN	I REMARKS I
NO.I LEVEL I NUMBER I		1

*		
*	THIS MAJOR NUMBER ALSO USED FOR TEST/FAULT LOC AFTER MAJOR 99	:
*		

57 00	BRANCH TO MAJOR 57 MINOR 3
57 01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
57 02	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
57 03	END OF MAJOR TEST

TESTICECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
58 00 58 01 58 02 58 03	BRANCH TO MAJOR 58 MINOR 3 Stop Tape, Display C Register, NO-GO Light on Stop Tape, Display C Register, NO-GO Light on END OF MAJOR TEST	

TESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS I
TICSTICECTSTON I TEST/FAULT I	SECI-IEST PROGRAM	I NEHARRS 1
NO_1_LEVEL1NUMBER1		I I I
		······································

59 00	BRANCH TO MAJOR 59 MINOR 3
59 01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
59 02	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
59 03	END OF MAJOR TEST

NO_1_LEVEL	TEST/FAULT	SELF-TEST PROGRAM	REMARKS
	**********	*******	****
:	•		*
	*	GSPU SECTION TESTS Majors 60 & 61 tests t285 - t304	*
1	•		•
1	************	***************************************	********
0 00		INITIALIZE	
		DEFINE SELF TEST TAPE Set inhibit increment CP flag & enable self test ncu clock mode (gtc003+)	
		ENABLE LOW LEVEL ON GTC001*	
		BRANCH TO MAJOR 60 MINOR 3	
0 01		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
0 02		INITIALIZE	
		DEFINE SELF TEST TAPE Set inhibit increment CP flag & enable self test nou clock mode	
		(GTC003+) Enable low level on gtc001+	
0 03 1	T285	TEST +DELTA_VX> DELTA_WX => COUNT UP AT 6.25 KHZ TO = 3	
		PREVIOUS TEST = (53)T283	
0 04		INITIATE GSPU CONTROL # 1	
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F000	EA=0374 1/0 REQ
		SERIALLY LOAD THE B REGISTER WITH A0000088	SET UP GSPU CONTROL WORD G1G2#+G5
		INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF0FFD	GSPU CLK TEST
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A40600 Load discrete input word (Eip/Eop Code) with A40400	EA=0401 I/O REQ
		INITIATE GSPU CONTROL # 3	I/O REQ
		ENABLE CONTROLLED TIMING PULSE INTERVAL 959 ON GTC001*	
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 Load discrete input word (Eip/Eop Code) with A3F400	EA=0375 I/D REQ
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH ASFA00	EA=0376
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F800	I/O REQ
		COMPARE THE B REGISTER TO A0000003 Branch to major 60 minor 5 on no-go Branch to major 60 minor 59	CHECK COUNT -> BREG
0 05 2	T285.N	REPEAT TEST T285	
0 06		INITIATE GSPU CONTROL # 1	
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200	EA=0374
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F000 Serially load the B register with A0000088	I/O REQ
		Startest cond the D Redigter with AUGUUU00	SET UP GSPU CONTROL WORD

NO.L LEVEL	I TEST/FAULT	SELF-TEST PROGRAM	REMARKS
			G1G2*+G5
		INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFFOFFD	GSPU CLK TEST
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A40600	EA=0401
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A40400	I/O REQ
		INITIATE GSPU CONTROL # 3	170 RC
		ENABLE CONTROLLED TIMING PULSE INTERVAL 959 ON GTCOO1+	
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600	EA=0375
		LOAD DISCRETE INPUT WORD (EIP/EDP CODE) WITH A3F400	1/0 REQ
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH ASFA00	EA=0376
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F800	I/O REQ
		COMPARE THE B REGISTER TO A000003	CHECK COUNT -> BREG
		BRANCH TO MAJOR 60 MINOR 7 ON NO-GO	CHECK COURT -> OKEG
		BRANCH TO MAJOR 60 MINOR 59	
0 07 3	T205 M		
	T285.NN	CHECK FOR NO TRANS GSPU -> BREG	
0 08		COMPARE THE B REGISTER TO A0000088	CONTROL CODE OF T285
		BRANCH TO MAJOR 60 MINOR 43 ON NO-GO	
		BRANCH TO MAJOR 60 MINOR 12	
0 09		SPARE	
0 10		SPARE	
0 11		SPARE	
0 12 4	T285.NNG	TEST +DELTA_VY> DELTA_WZ => COUNT UP AT 6.25 KHZ TO = 3	
0 13		INITIATE GSPU CONTROL # 1	
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200	EA=0374
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F000	I/O REQ
		SERIALLY LOAD THE B REGISTER WITH A0000028	GSPU CONTROL WD = G3G4++G
		INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFFOFFD	GSPU CLK TEST
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A41200	EA=0404
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A41000	I/O REQ
		INITIATE GSPU CONTROL # 3	
		ENABLE CONTROLLED TIMING PULSE INTERVAL 959 ON GTCOO1*	
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600	EA=0375
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400	I/O REQ
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3FA00	EA=0376
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F800	I/O REQ
		COMPARE THE B REGISTER TO A0000003	CHECK COUNT -> BREG
		BRANCH TO MAJOR 60 MINOR 14 ON NO-GO	
5	F285.NNGG	FAULT IN +DELTA VX> DELTA WX => COUNT = 3	
5	F285.NNGG	FAULT IN +DELTA_VX> DELTA WX => COUNT = 3 ENABLE VERTICAL PARITY CHECK	

TESTIC		I TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
			IINDIGATORSISPLAYREPLACE_ASSEMBLIESI INO GOIBLANK  2A1A1A18 II2A1A2A(14,16) II2A1A3A15_6,7]	AGB211* SƏ1
50 14 50 15	5	T285.NNGN	TEST DECODE OF COUNTER = 66, COUNT UP AT 50 KHZ => TRANS COUNT -> BREG SERIALLY LOAD THE B REGISTER WITH A0000008 INITIATE GSPU CONTROL # 2	GSPU CONTROL WD = G5
			LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F000 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F800 COMPARE THE 8 REGISTER TO A0000043 BRANCH TO MAJOR 60 MINOR 16 ON NO-GO	EA=0374 I/O REQ EA=0375 I/O REQ EA=0376 I/O REQ
			BRANCH TO MAJOR 60 MINOR 37	
50 16 50 17	6	T2 85 . NNGNN	TEST FOR NO TRANS GSPU -> BREG Compare the B register to a0000008 Branch to Major 60 minor 21 on NO-Go Branch to Major 60 minor 31	CONTROL CODE OF T285.NNN
50 18 50 19			SPARE SPARE	
60 20			SPARE	
50 21	7	T285.NNGNN >N	TEST DECODE OF COUNTER = 223, COUNT UP AT 50 KHZ => TRANS COUNT -> BREG, Control wd inactive	
50 22			SERIALLY LOAD THE B REGISTER WITH A Initiate GSPU control # 2	GSPU CONTROL WO INACTIVE
			LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F000 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F800 COMPARE THE B REGISTER TO A00000E0 BRANCH TO MAJOR 60 MINOR 23 ON NO-GO	EA=0374 I/O REQ EA=0375 I/O REQ EA=0376 I/O REQ
	8	F285. NNGNN >NG	FAULT IN EN OF GSPU CONTROL WORD Enable vertical parity check Stop tape, display c register, nd-go light on	

TESTIDECISION		SELF-TEST PROGRAM	I REMARKS
I_NO_L_LEVEL	INUMBER		
		I INDICATORS I DISPLAY I REPLACE ASSEMBLIES	
		IND GO I BLANK IZA1A1A18	AGC110
50 23 8	T285.NNGNN >NN	TEST -DELTA_VY> QUU223*(S.T.REC) => COUNT DOWN AT FULL RATE OF 100 KH	
60 24		SERIALLY LOAD THE B REGISTER WITH A0000038	GSPU CONTROL WD = G3G4+G5
		INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFFOFFD	GSPU CLK TEST
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F000	EA=0374 I/O REQ
		INITIATE GSPU CONTROL # 3	ITO REQ
		ENABLE CONTROLLED TIMING PULSE INTERVAL 971 ON GTCOO1*	
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600	EA=0375
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3FA00	1/0 REQ EA=0376
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH ASF800	I/O REQ
		COMPARE THE B REGISTER TO A00000CF	
		BRANCH TO MAJOR 60 MINOR 25 ON NO-GO	
9	F285.NNGNN		
	>NNG	NO RESET OF GSP3 LATCH	
		ENABLE VERTICAL PARITY CHECK	
		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		INDICATORS I DISPLAY L REPLACE ASSEMBLIES	
		I NOGO	AGCO10 SƏ1
60 25 9	F285.NNGNN		
	>NNN	FAULT IN EOP RESET GSPU OR AGC309* TIMING	
		ENABLE VERTICAL PARITY CHECK	
		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		I_INDICATORSI_DISPLAYIBEPLACE_ASSEMBLIES	
		NO GO   317 2A1A2A14	AGC613# S@1
		IIIIIXXXI2A1A3A(5,16)	AGC309+
			A0C307+
60 26		SPARE	
60 27		SPARE	
60 28		SPARE	
60 <b>29</b>		SPARE	
60 30		SPARE	
60 31 7	T285.NNGNN		
	>G	TEST AGC309* => 1/0 CMPLT, GTC010 -> QUT009 ON AGC309*	
60 32		SERIALLY LOAD THE B REGISTER WITH A0080008	GSPU CONTROL WD = G5

TESTIDEC		TEST/FAULT NUMBER	I SELF-TEST PROGRAM	I REMARKS
			INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OF9FFOFFF INITIATE GSPU CONTROL # 2 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3FA00 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3FA00 BISCRETE INPUT WORD (EIP/EOP CODE) WITH A3FA00 COMPARE THE B REGISTER TO A LOGICALLY 'AND' C REGISTER AND A008 - RESULT IN B & C REGISTER BRANCH TO MAJOR 60 MINOR 33 ON NO-GO	MTW1->INMX ON AGC309* EA=0374 EA=0375 I/O REQ EA=0376 I/O REQ
8	I	F285.NNGNN >GG	INPUT TO ARKO19 OPEN ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GOIBLANKI2A1A1A02I	
0338	I	F285.NNGNN >GN	FAULT IN GSPU -> BREG         ENABLE VERTICAL PARITY CHECK         STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON         Indicators         Inditenter         Indit	AGC309* SƏ1
0 34 0 35 0 36			SPARE SPARE SPARE	
0376 038		₹285•NNGNG	TEST -DELTA_VY> QUU223*(S.T.REC) => COUNT DOWN AT FULL RATE OF 100 KHZ SERIALLY LOAD THE B REGISTER WITH A00000038 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF0FFD LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200 INITIATE GSPU CONTROL # 3 ENABLE CONTROLLED TIMING PULSE INTERVAL 971 ON GTC001* LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600	GSPU CONTROL WD = G3G4+G5 GSPU CLK TEST EA=0374 I/O REQ EA=0375 I/O REQ EA=0376 I/O REQ
7	,	F285.NNGNG >G	FAULT IN GSP1 IBT OR LATCH ENABLE VERTICAL PARITY CHECK	

ENABLE VERTICAL PARITY CHECK

TESTIDECISION		I SELF-TEST PROGRAM	REMARKS
		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		INDICATORS DISPLAY REPLACE ASSEMBLIES	
		IND GD I BLANK IZA1AZA12	AGC624 OR CGB028 S@0
		11111112A1A3A(2+3+4+5)1	
		·	
0397	F285.NNGNG		
	>N	FAULT IN GSP3 IBT OR LATCH $\pm$ > EN GSPU CONTROL WD	
		ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		I INDICATORS 1 DISPLAY 1 REPLACE ASSEMBLIES	
			BGC009* S@1
		ll2A1A3A(4,5)l	
0 40		SPARE	
C 41 O 42		SPARE SPARE	
0 42		SPARE	
0 43 4	T2 85. NNN	TEST DECODE OF COUNTER = 66, COUNT UP AT 50 KHZ => TRANS COUNT -> BREG	
0 44	1203-1111	SERIALLY LOAD THE B REGISTER WITH A0000008	GSPU CONTROL WD = G5
		INITIATE GSPU CONTROL # 2	
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200	EA=0374
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600	EA=0375
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400	I/O REQ
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3FA00	EA=0376
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F800	I/O REQ
		COMPARE THE B REGISTER TO A0000043	
		BRANCH TO MAJOR 60 MINOR 45 ON NO-GO Branch to major 60 minor 51	
0455	T 2 85 . NNNN	TEST -DELTA_VY> QUU223*(S.T.REC) => COUNT DOWN AT FULL RATE OF 100 KHZ	,
0 46	1203011111	SERIALLY LOAD THE B REGISTER WITH A0000038	GSPU CONTROL WD = G3G4+G5
		INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFFOFFD	GSPU CLK TEST
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200	EA=0374
		LOAD DISCRETE INPUT WORD (EIP/EDP CODE) WITH A3F000	I/O REQ
		INITIATE GSPU CONTROL # 3	
		ENABLE CONTROLLED TIMING PULSE INTERVAL 971 ON GTCOOL*	
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600	EA=0375
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400	I/O REQ
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3FA00	EA=0376
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F800 Compare the B register to A00000CF	I/O REQ
		BRANCH TO MAJOR 60 MINOR 47 ON NO-GO	
4		FAULT IN GENERATION OF 6.25 KHZ & 50 KHZ, OR UP/DOWN CONTROL	
6	F285.NNNNG	ENABLE VERTICAL PARITY CHECK	

ENABLE VERTICAL PARITY CHECK Stop tape, display c register, nd-go light on

TESTICECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS I
I_NOAL_LEVEL_INUMBERI		······································

INDICATORS	I DISPLAY	IREPLACE_ASSEMBLIESI
INO_GO	I BLANK	12A1A3A(1+2+3+4+5+16) 1

60 47	6	T285.NNNNN	TEST DECODE OF COUNTER = 223, COUNT UP AT 50 KHZ => TRANS COUNT -> BREG,	
			CONTROL WO INACTIVE	
60 48			SERIALLY LOAD THE B REGISTER WITH A	GSPU CONTROL WD INACTIVE
			INITIATE GSPU CONTROL # 2	
			LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200	EA=0374
			LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F000	I/O REQ
			LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600	EA=0375
			LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400	I/O REQ
			LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3FA00	EA=0376
			LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F800	I/O REQ
			COMPARE THE B REGISTER TO A00000E0	
			BRANCH TO MAJOR 60 MINOR 49 ON NO-GO	

F285.NNNNN	
>G	FAULT IN GSPU CONTROL WORD
	ENABLE VERTICAL PARITY CHECK
	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON

	REPLACE_ASSEMBLIES
	L2A1A1A18

60 49	7	F285.NNNNN	
		>N	FAULT IN GSPU COUNTER, CLOCK GENERATOR, OR COUNTER RESET
			ENABLE VERTICAL PARITY CHECK

STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON

INDICATOR	SI_DI SPLAYI	REPLACE ASSEMBLIE	<u>s</u> ł	
INO GO	XXX 2A1A2A		I	
I	I12A1A3#	A(1+2+3+4+6)		
NO_GO	601241A3A	A(2.4.5.7.10)	I "COUNT U	p sai

60 50 SPARE

60 51	5	T285.NNNG	TEST -DELTA_VY> QUU223*(S.T.REC) => COUNT DOWN AT FULL RATE OF 100 KHZ	
60 52			SERIALLY LOAD THE <b>B</b> R <b>EG</b> ISTER WITH A0000038	GSPU CONTROL WD = G3G4+G5
			INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFFOFFD	GSPU CLK TEST
			LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200	EA=0374
			LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F000	I/O REQ
			INITIATE GSPU CONTROL # 3	
			ENABLE CONTROLLED TIMING PULSE INTERVAL 971 ON GTCOO1*	
			LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600	EA=0375
			LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400	I/O REQ
			LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3FA00	EA=0376
			LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F800	I/O REQ

		I TEST/FAULT	I SELF-TEST PROGRAM	REMARKS
			COMPARE THE B REGISTER TO A00000CF Branch to Major 60 minor 53 on ND-GD	
	6	F285.NNNGG	FAULT IN 6.25 KHZ CLOCK RATE Enable vertical parity check Stop Tape, Display C register, ND-GO light on	
			I INDICATORS I DISPLAY I REPLACE ASSEMBLIES	   BGC305*
53	6	F285+NNNGN	FAULT IN CLOCK COUNTER,OR CLOCK WINDOW EN ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
			IINDIGATORSI_DISPLAY_IREPLACE_ASSEMBLIES NO GO   31712A1A1A07      2A1A2A12     2A1A2A12	
			12A1A3A(3.4.6)  NO_GO1XXX 1A1A3A(6.7.8.9.10.11)	BKF034*
54			SPARE	
55 56			SPARE SPARE	
57			SPARE	
58			SPARE	
59	1	T286 T285.NG	TEST -DELTA_VX> DELTA WY => COUNT UP AT 6.25 KHZ TO = 3	
60			INITIATE GSPU CONTROL # 1	
			LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200	EA=0374
			LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F000 Serially load the B register with A00000c8	I/O REQ GSPU CONTROL WD = G1G2+G
			INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFFOFFD	GSPU CLK TEST
			LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A40A00	EA=0402
			LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A40800 Initiate GSPU control # 3	I/O REQ
			ENABLE CONTROLLED TIMING PULSE INTERVAL 959 DN GTCODI#	
			LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600	EA=0375
			LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 Load discrete input word (Eip/Eop Code) with A3FA00	I/O REQ EA=0376
			LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F800	I/O REQ
			COMPARE THE B REGISTER TO A0000003 Branch to major 60 minor 61 on NO-Go Branch to major 60 minor 67	CHECK COUNT -> BREG
		T286.N	REPEAT TEST T286	
61	2	120001	INITIATE GSPU CONTROL # 1	

TESTIDECISION		SELF-TEST PROGRAM	I REMARKS
I <u>NO.I</u> E¥EL	I NUMBER	LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F000 SERIALLY LOAD THE B REGISTER WITH A00000C8 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF0FFD LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A40800 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A40800 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 SCOMPARE THE B REGISTER TO A0000003 BRANCH TO MAJOR 60 MINOR 63 ON NO-GO BRANCH TO MAJOR 60 MINOR 67	I/O REQ GSPU CONTROL WD = G1G2+G5 GSPU CLK TEST EA=0402 I/O REQ EA=0375 I/O REQ EA=0376 I/O REQ CHECK COUNT -> BREG
60 63 3	F286•NN	FAULT IN -DELTA_VX> DELTA WY => COUNT = 3 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYI	 AGB213* SƏ1
60 64 60 65 60 66		SPARE SPARE SPARE SPARE	<del>_</del>
60 67 1 60 68	T287 T286∙NG	TEST +DELTA_VY> DELTA_WZ => COUNT UP AT 6.25 KHZ TO = 3 INITIATE GSPU CONTROL # 1 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F000 SERIALLY LOAD THE B REGISTER WITH A0000028 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF0FFD LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A41200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A41200 INITIATE GSPU CONTROL # 3 FNABLF CONTROLLED TIMING PULSE INTERVAL 959 ON GTCOO1*	EA=0374 I/O REQ GSPU CONTROL WD = G3G4*+G5 GSPU CLK TEST EA=0404 I/O REQ
60 69 2 60 70	T287•N	LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3FA00 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F800 COMPARE THE B REGISTER TO A0000003 BRANCH TO MAJOR 60 MINOR 69 ON NO-GO BRANCH TO MAJOR 60 MINOR 75 REPEAT TEST T287 INITIATE GSPU CONTROL # 1 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200 SERIALLY LOAD THE B REGISTER WITH A0000028	EA=0375 I/O REQ EA=0376 I/O REQ CHECK COUNT -> BREG EA=0374 I/O REQ GSPU CONTROL WD = G3G4*+G5

ITESTICE	CISION   TE	ST/FAULT   NUMBERL	SELF-TEST PROGRAM	I REMARKS
			INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFFOFFD LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A41200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A41000 INITIATE GSPU CONTROL # 3	GSPU CLK TEST EA=0404 I/O REQ
			ENABLE CONTROLLED TIMING PULSE INTERVAL 959 ON GTCOOL* LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3FA00 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3FA00 COMPARE THE B REGISTER TO A0000003 BRANCH TO MAJOR 60 MINOR 71 ON NO-GO BRANCH TO MAJOR 60 MINOR 75	EA=0375 I/O REQ EA=0376 I/O REQ CHECK COUNT -> BREG
60 71	3 F28	7•NN F	AULT IN +DELTA_VY> DELTA_WZ => COUNT = 3 Enable vertical parity check Stop tape, display c register, nd-go light on	
			I       I       DISPLAY       I       BEPLACE ASSEMBLIES         IND GO       I       53[2A1A1A18         I       I       12A1A2A(14,16)         I       I       I2A1A3A(1,5,6,7)	   AGB215* SƏ1 
60 72 60 73 60 74		5	SPARE Spare Spare	
60 75 60 76	1 T28 T28		TEST GSPU CONTROL WORD = G3G4++G6 => +DELTA_VY -> DELTA_WZ => COUNT = 3 INITIATE GSPU CONTROL # 1	
			LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F000 SERIALLY LOAD THE B REGISTER WITH A0000024 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF0FFD LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A41200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A41000 INITIATE GSPU CONTROL # 3	EA=0374 I/O REQ GSPU CONTROL WD = G3G4*+G6 GSPU CLK TEST EA=0404 I/O REQ
			ENABLE CONTROLLED TIMING PULSE INTERVAL 959 ON GTCOOI* LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F800 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F800 COMPARE THE B REGISTER TO A0000003 BRANCH TO MAJOR 60 MINOR 77 ON NO-GO BRANCH TO MAJOR 60 MINOR 80	EA=0375 I/O REQ EA=0376 I/D REQ CHECK COUNT -> BREG
60 77 60 78	2 T28	38•N F	REPEAT TEST T288 INITIATE GSPU CONTROL # 1 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F000 SERIALLY LOAD THE B REGISTER WITH A0000024	EA=0374 I/O REQ GSPU CONTROL WD = G3G4*+G6

TEST CECISION	TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
		INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF0FF0 Load discrete input word (EIP/EOP Code) with A41200 Load discrete input word (EIP/EOP Code) with A41000 Initiate GSPU control # 3	GSPU CLK TEST E <b>A=0404</b> I/O REQ
		ENABLE CONTROLLED TIMING PULSE INTERVAL 959 ON GTCOOI* LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 COMPARE THE B REGISTER TO A0000003 BRANCH TO MAJDR 60 MINOR 79 ON NO-GO BRANCH TO MAJDR 60 MINOR 80	EA=0375 I/O REQ EA=0376 I/O REQ CHECK COUNT -> BREG
0793	F288.NN	FAULT IN GSPU G6 ENABLE VERTICAL PARITY CHECK	
		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON  I	 _  _  AGD006* Sal
		III2AIA3A05 INO GO I XXXI2AIAIAI8 II2AIA3A05	AGD006*
50 80 1	T289		
50 81	T288.NG	TEST AGC309* => I/O CMPLT, GTC010 -> QUT009 ON AGC309* Serially Load the B register with A0000008 Initiate self test mode 2-load self test register with of9fffofff	GSPU CONTROL WD = G5 MTW1->INMX ON AGC309*
		INITIATE GSPU CONTROL # 2 Load discrete input word (EIP/EOP Code) with A3F200	EA=0374
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F000	I/D REQ
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600	EA=0375
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400	I/O REQ
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3FAOO Load discrete input word (Eip/Eop Code) with A3F800	EA=0376 I/O REQ
		COMPARE THE B REGISTER TO A LOGICALLY 'AND' C REGISTER AND A0080008 - RESULT IN B & C REGISTER BRANCH TO MAJOR 60 MINOR 82 ON NO-GO BRANCH TO MAJOR 60 MINOR 93	
60 82 2 60 83	T289.N	TEST FOR NO GSPU -> BREG Compare the B register to A0000008 Branch to Major 60 Minor 84 on NO-Go Branch to Major 60 Minor 88	
60 84 3	F289.NN	FAULT IN GSPU I/N ACKNOWLEDGE ENABLE VERTICAL PARITY CHECK	

TESTICECISION	I TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
		IREPLACE_ASSEMBLIES NO GO I 20000012A1A2A12 I LI2A1A3A(4.5)	IGC503* \$@1
) 85 ) 86 ) 87		SPARE SPARE SPARE	
D 88 3 D 89	T289.NG	TEST GSPU UP/DOWN COUNTER DECODE AT 60, COUNT UP AT 50 KHZ SERIALLY LOAD THE B REGISTER WITH A0000004 INITIATE GSPU CONTROL # 2 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F800 COMPARE THE B REGISTER TO A000003D BRANCH TO MAJOR 60 MINOR 90 ON NO-GO	GSPU CONTROL WD = G6 EA=0374 I/O REQ EA=0375 I/O REQ EA=0376 I/O REQ
4	F289.NGG	FAULT IN COUNTER ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDIGATORSI_DISPLAYI	KGADOZ UR KGADO7
0904	F289.NGN	FAULT IN COUNTER DECODE SEQUECE         ENABLE VERTICAL PARITY CHECK         STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON         INDICATORS       I DISPLAY         INDICATORS       I DISPLAY         IND GO       71/2A1A2A01         I2A1A3A12.4.5.6.7.16)	   KGC210* S∂0 
0 91 0 92		SPARE SPARE	
0931 094	T 2 90	TEST DECODE OF COUNTER = 223, COUNT UP AT 50 KHZ => TRANS COUNT -> BREG, CONTROL WD INACTIVE SERIALLY LOAD THE B REGISTER WITH A INITIATE GSPU CONTROL # 2 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F000 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400	GSPU CONTROL WD INACTIV EA=0374 I/O REQ EA=0375 I/O REQ

ITESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	REMARKS
	LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3FA00 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F800 Compare the B register to A00000E0 Branch to Major 60 minor 95 on NO-GO Branch to Major 60 minor 98	EA=0376 1/0 REQ
60 95 2 F290.N	FAULT IN DECODE OF 223 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
	IINDICATORSI_DISPLAYREPLACE_ASSEMBLIES NO_GOI34112A1A3A12.4.5.71 NO_GOIXXXI2A1A3A12.3.4.5.71	I AGC 204*
60 96 60 97	SPARE Spare	

60 98	ENABLE VERTICAL PARITY CHECK
60 99	END OF MAJOR TEST

		1 TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
<b>51 00</b>			INITIALIZE CEFINE SELF TEST TAPE SET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST NCU CLOCK MODE (GTC003*) ENABLE LOW LEVEL ON GTC001* BRANCH TO MAJOR 61 MINOR 3	
1 01 1 02			STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
03 04 04	1	T 2 9 1	TEST DECODE OF COUNTER = 66, COUNT UP AT 50 KHZ => TRANS COUNT -> BREG SERIALLY LOAD THE B REGISTER WITH A0000008 INITIATE GSPU CONTROL # 2 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F000 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F800 COMPARE THE B REGISTER TO A0000043 BRANCH TO MAJOR 61 MINOR 5 ON NO-GO BRANCH TO MAJOR 61 MINOR 9	GSPU CONTROL WD = G5 EA=0374 I/O REQ EA=0375 I/O REQ EA=0376 I/O REQ I/O REQ
1 05	2	F291.N	FAULT IN DECODE OF COUNT 66 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I INDICATORS I DISPLAY I REPLACE ASSEMBLIES NO GO I XXXIZAIAIAI8 I ILLIII IILLIII ILLIII IZAIAJAI4.5.7]	
1 06 1 07 1 08			SPARE SPARE SPARE	
51 09 51 10	1	T292	TEST GSPU UP/DGWN COUNTER DECODE AT 60, COUNT UP AT 50 KHZ SERIALLY LOAD THE B REGISTER WITH A0000004 INITIATE GSPU CONTROL # 2 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F000 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 BRANCH TO MAJOR 61 MINOR 11 ON NO-GO BRANCH TO MAJOR 61 MINOR 15	GSPU CONTROL WD = G6 EA=0374 I/D REQ EA=0375 I/O REQ EA=0376 I/O REQ

NO.I LEVEL	TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
51 11 2	F292.N	FAULT IN DECODE OF 60 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		I <u>INDICATORS I DISPLAY I</u> <u>REPLACE ASSEMBLIES</u> IND GO I <u>XXX</u> [2A1A1A18 I <u>I</u> 2A1A3A(2.4.5.7]	
51 12 51 13 51 14		SPARE SPARE SPARE	
51 15 1 51 16	τ293	TEST GSPU UP/DOWN COUNTER DECODE AT 111, COUNT UP AT 50 KHZ SERIALLY LOAD THE 8 REGISTER WITH A0000002 INITIATE GSPU CONTROL # 2 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 BRANCH TO MAJOR 61 MINOR 17 ON NO-GO BRANCH TO MAJOR 61 MINOR 21	GSPU CONTROL WD = G7 EA=0374 I/O REQ EA=0375 I/O REQ EA=0376 I/O REQ
51 17 2	F293.N	FAULT IN DECODE OF 111 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT DN I	
51 18 51 19 51 20		SPARE SPARE SPARE	
51 21 1 51 22	T294	TEST -DELTA_VY> QUU223*(S.T.REC) => COUNT DOWN AT FULL RATE OF 100 KHZ SERIALLY LOAD THE B REGISTER WITH A0000038 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF0FFD LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200 INITIATE GSPU CONTROL # 3 ENABLE CONTROLLED TIMING PULSE INTERVAL 971 ON GTCOO1* LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400	GSPU CONTROL WD = G3G4+G5 GSPU CLK TEST EA=0374 I/O REQ EA=0375 I/O REQ EA=0376 I/O REQ

ND.1_LEV	ION   TEST/FAULT ELNUMBER	SELF-TEST PROGRAM	1 REMARKS
		COMPARE THE B REGISTER TO ACCOCCF Branch to major 61 minor 23 on ND-GO Branch to major 61 minor 29	
1232 124	T294•N	TEST FOR COUNTER AT ZERO Compare the B register to A Branch to Major 61 Minor 25 on ND-GO	
3	F294•NG	FAULT IN COUNT DOWN CONTROL OR 100 KHZ CLK TO COUNTER Enable vertical parity check Stop Tape, display c register, no-go light on	
		INDICATORS L DISPLAY 1 REPLACE ASSEMBLIES NO GO I BLANK IZAIAIAI8 II ZAIAJAI5.6.7.8)	
1253	F294 • NN	COUNTER FAULT WHEN COUNT DOWN ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES IND_GOIXXX12A1A3A(2+3+4)	
1 26 1 27 1 28		SPARE SPARE SPARE	
1291 130	T 2 9 5	TEST COUNT DOWN AT 1/2 RATE, -DELTA_VY> QUU223*(S.T.REC) SERIALLY LOAD THE B REGISTER WITH A0000032 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF0FFD LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200 INITIATE GSPU CONTROL # 3	GSPU CONTROL WD = G3G4+G7 GSPU CLK TEST EA=0374 I/O REQ
		ENABLE CONTROLLED TIMING PULSE INTERVAL 951 ON GTCOO1* LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3FA00 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F800 COMPARE THE B REGISTER TO A00000E5 BRANCH TO MAJOR 61 MINOR 31 ON NO-GO BRANCH TO MAJOR 61 MINOR 37	EA=0375 I/O REQ EA=0376 I/O REQ
1312	T295.N	REPEAT TEST T295 Test count down at 1/2 rate, -delta_vy> quu223*(S.t.rec)	
1 32		SERIALLY LOAD THE B REGISTER WITH A0000032 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF0FFD LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F000	GSPU CONTROL WD = G3G4+G GSPU CLK TEST EA=0374 I/D REQ

TESTICECISION	TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
		INITIATE GSPU CONTROL # 3 ENABLE CONTROLLED TIMING PULSE INTERVAL 951 ON GTC001* LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F800 COMPARE THE B REGISTER TO A00000E5 BRANCH TO MAJOR 61 MINOR 33 ON NO-GO BRANCH TO MAJOR 61 MINOR 37	EA=0375 I/O REQ EA=0376 I/O REQ
133 3	F295.NN	FAULT IN 1/2 RATE CONTROL ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT UN I INDICATORS I DISPLAY I REPLACE ASSEMBLIES NO GO	AGB024*
ol 34 ol 35 ol 36		SPARE SPARE SPARE	
51 37 1 51 38	T296 T296.NG	TEST COUNT DOWN AT 1/16 RATE, -DELTA_VY> QUU223*(S.T. REC) SERIALLY LOAD THE B REGISTER WITH A0000031 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFFOFFD LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F000 INITIATE GSPU CONTROL # 3 ENABLE CONTROLLED TIMING PULSE INTERVAL 951 ON GTC001* LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 LOAD DISCRETE INPUT A3F60 MINOR 43	GSPU CLK TEST EA=0374 I/O REQ EA=0375 I/O REQ EA=0376 I/O REQ
51 39 2	F296.N	FAULT IN 1/16 RATE CONTROL Enable vertical parity check Stop Tape, display c register, nd-go light on	

TESTIDECISION	TEST/FAULT  NUMBEB	I SELF-TEST PROGRAM	1 REMARKS
		I INDICATORS I DISPLAY I REPLACE ASSEMBLIES NO GO I XXXI 24141418 I IZA143411.5,6.131	   CGB025* SƏ1 
1 40 1 41 1 42		SPARE SPARE SPARE	
1 43 1	T2 97	TEST FOR ACTIVE RECEIVERS OR DRIVERS OF GSPU SECTION >DELTA_WX , -DELTA_VY>	
1 44		INITIATE GSPU CONTROL # 1 LGAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F000 SERIALLY LOAD THE B REGISTER WITH A0000038 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF0FFD LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A40600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A40600 INITIATE GSPU CONTROL # 3 ENABLE CONTROLLED TIMING PULSE INTERVAL 959 ON GTCOOL* LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 LOAD DISCRETE INPUT A000 61 MINOR 49	EA=0374 I/O REQ GSPU CONTROL WD = G3G4+G5 GSPU CLK TEST EA=0401 I/O REQ EA=0375 I/O REQ EA=0376 I/O REQ
<b>1 45</b> 2	F297.N	XTK220+ OR CGB006+ ACTIVE ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES INO GO I XXX   2 A1 A1 A18 IIZA1A3A16.7.8}	- 1 1 - 1
ol 46 51 47 51 48		SPARE SPARE SPARE	
51 49 1 51 50	T298	TEST FOR ACTIVE RECEIVERS OR DRIVERS OF GSPU SECTION > DELTA_WY + -DELTA_VX> INITIATE GSPU CONTROL # 1 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F000 SERIALLY LOAD THE B REGISTER WITH A00000C8 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF0FFD LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A40600	EA=0374 I/O REQ GSPU CONTROL WD = G1G2+G5 GSPU CLK TEST EA=0+01

TESTICECISION		I SELF-TEST PROGRAM	I REMARKS
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A40400 INITIATE GSPU CONTROL # 3 ENABLE CONTROLLED TIMING PULSE INTERVAL 959 ON GTCO01* LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F800 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F800 COMPARE THE B REGISTER TO A00000C8 BRANCH TO MAJOR 61 MINOR 51 ON NO-GO BRANCH TO MAJOR 61 MINOR 55	I/O REQ EA=0375 I/O REQ EA=0376 I/O REQ
51 51 2	F298.N	XTK220* OR IED402 ACTIVE ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYI	- - - - -
61 52 61 53 61 54		SPARE SPARE SPARE	
61 55 1 61 56	Τ299	TEST FOR ACTIVE RECEIVERS OR DRIVERS OF GSPU SECTION > CELTA_WY , +CELTA_VX> INITIATE GSPU CONTROL # 1 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F000 SERIALLY LOAD THE B REGISTER WITH A0000088 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFOFFD LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A40A00 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A40A00 INITIATE GSPU CONTROL # 3 ENABLE CONTROLLED TIMING PULSE INTERVAL 959 ON GTCOO1* LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F800 COMPARE THE B REGISTER TO A0000088 BRANCH TO MAJOR 61 MINOR 57 ON NO-GO BRANCH TO MAJOR 61 MINOR 61	EA=0374 I/O REQ SET UP GSPU CONTROL WORD = G1G2*+G5 GSPU CLK TEST EA=0402 I/O REQ EA=0375 I/O REQ EA=0376 I/O REQ
61572	F299.N	XTK221* OR IED401 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	

TESTIDECISION		SELF-TEST PROGRAM	I REMARKS
		IINDICATORSI_DISPLAYI	
61 58 61 59 51 60		SPARE SPARE SPARE	
61 61 1	T300	TEST FOR ACTIVE RECEIVERS OR DRIVERS OF GSPU SECTION > delta_wy , g2* => no driver active	
51 62		INITIATE GSPU CONTROL # 1 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F000 SERIALLY LOAD THE B REGISTER WITH A0000048 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF0FFD LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A40A00 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A40A00 INITIATE GSPU CONTROL # 3 ENABLE CONTROLLED TIMING PULSE INTERVAL 959 ON GTC001* LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3FA00 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3FB00 COMPARE THE B REGISTER TO A0000048 BRANCH TO MAJOR 61 MINOR 67	EA=0374 I/O REQ GSPU-CONTROL WD = G2+G5 GSPU-CLK TEST EA=0402 I/O REQ EA=0375 I/O REQ EA=0376 I/O REQ
61632	F300.N	INPUT TO CGB021* OPEN ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYI	1
61 64 61 65		SPARE SPARE	
61 66		SPARE	
61 67 1 61 68	T301	TEST FOR ACTIVE RECEIVERS GR DRIVERS OF GSPU SECTION > DELTA_WZ , -DELTA_VY INITIATE GSPU CONTROL # 1 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F000 SERIALLY LOAD THE B REGISTER WITH A0000038 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF0FFD LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A41200	EA=0374 I/O REQ GSPU CONTROL WD = G3G4+G5 GSPU CLK TEST EA=0404

TESTICECISION   TEST/FAULT	I SELF-TEST PROGRAM	1 REMARKS 1
	LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A41000 INITIATE GSPU CONTROL # 3 ENABLE CONTROLLED TIMING PULSE INTERVAL 959 ON GTCOOI* LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F400 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F800 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F800 COMPARE THE B REGISTER TO A0000038 BRANCH TO MAJOR 61 MINOR 69 ON NO-GO BRANCH TO MAJOR 61 MINOR 73	I/O REQ EA=0375 I/O REQ EA=0376 I/O REQ
61 69 2 F301.N	INPUT TO CGB022+ OPEN ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDIGATORSI_DISPLAYIREPLACE_ASSEMBLIES IND_GOIXXX12A1A3A06	 
61 70 61 71 61 72	SP AR E SP AR E SP AR E	
61 73 1 T302 61 74	TEST FOR ACTIVE RECEIVERS OR DRIVERS OF GSPU SECTION > DELTA_WZ + -CELTA_VX +-> INITIATE GSPU CONTROL # 1 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F000 SERIALLY LOAD THE B REGISTER WITH A00000C8 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF0FFD LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A41200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A41000 INITIATE GSPU CONTROL # 3 ENABLE CONTROLLED TIMING PULSE INTERVAL 959 ON GTC001* LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 COMPARE THE B REGISTER TO A00000C8 BRANCH TO MAJOR 61 MINOR 75 ON NO-G0 BRANCH TO MAJOR 61 MINOR 79	EA=0374 I/O REQ GSPU CONTROL WD = G1G2+G5 GSPU CLK TEST EA=0404 I/O REQ EA=0375 I/O REQ EA=0376 I/O REQ
61 75 2 F302.N	XTK222* OR IED402 ACTIVE Enable vertical parity check Stop Tape, display c register, no-go light on	

TESTIDECISION		I SELF-TEST PROGRAM	I REMARKS
		IINDICAIOBS1_DISPLAY1	-1 -1 -1 -1
1 76 1 77 1 78		SPARE SPARE SPARE	
179 1	T303	TEST FOR ACTIVE RECEIVERS OR DRIVERS OF GSPU SECTION > DELTA_WX , +DELTA_VY> INITIATE GSPU CONTROL # 1 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F000 SERIALLY LOAD THE B REGISTER WITH A0000028 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFOFFD LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A40600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A40600 INITIATE GSPU CONTROL # 3 ENABLE CONTROLLED TIMING PULSE INTERVAL 959 ON GTCO01* LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600 COMPARE THE B REGISTER TO A0000028 BRANCH TO MAJOR 61 MINOR 85	EA=0374 I/O REQ GSPU CONTROL WD = G3G4*+0 GSPU CLK TEST EA=0401 I/O REQ EA=0375 I/O REQ EA=0376 I/O REQ
<b>5181</b> 2	F303.N	XTK220* OR IED404 ACTIVE ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI DISPLAY	- - - - -
1 82 1 83 1 84		SPARE SPARE SPARE	
51 85 1 51 86	T304	TEST INPUTS TO CGB023* AND INH OF DELTA_W RECEIVERS SERIALLY LOAD THE B REGISTER WITH A00000D8 INITIATE SELF TEST MODE 2~LOAD SELF TEST REGISTER WITH OFBFFF0FFD LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F200 LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F000 INITIATE GSPU CONTROL # 3	GSPU CONTROL WD = G1G2+G3*G4+G5 GSPU CLK TEST EA=0374 I/O REQ

TESTIDECISION	TEST/FAULT LNUMBER	1 SELF-TEST PROGRAM	1 REMARKS
		ENABLE CONTROLLED TIMING PULSE INTERVAL 971 ON GTCOO1* Load discrete input word (Eip/Eop Code) with A3F600	EA=0375
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH ASF600	1/0 REQ
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH ASFA00	EA=0376
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH ASF800	I/O REQ
		COMPARE THE B REGISTER TO A	
		BRANCH TO MAJOR 61 MINOR 87 ON NO-GO	
		BRANCH TO MAJOR 61 MINOR 91	
1872	F304.N	FAULT IN CGB023* OR DELTA_WX RECEIVER	
		ENABLE VERTICAL PARITY CHECK	
		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		INDICATORS I DISPLAY I REPLACE ASSEMBLIES	-1
		(NO GO ( XXX (2 A I A I A I B	1
		↓ ↓ZA1A2A(14,16)	l.
		III2A1A3A06	_1
188		SPARE	
1 89		SPARE	
1 90		SPARE	
1 91 1 1 92	T3 05	TEST INPUTS TO CGB023* AND INH OF DELTA_W RECEIVERS Serially load the B register with A00000A8	GSPU CONTROL WD = G1G2*+G3G4*+G5
		INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFFOFFD	GSPU CLK TEST
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH ASF200	EA=0374
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F000	I/O REQ
		INITIATE GSPU CONTROL # 3	
		ENABLE CONTROLLED TIMING PULSE INTERVAL 971 ON GTCOO1*	
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F600	EA=0375
		LOAD DISCRETE INPUT WORD (EIP/EDP CODE) WITH A3F400	I/O REQ
		LOAD DISCHETE INPUT WORD (EIP/EOP CODE) WITH A3FA00	EA=0376
		LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A3F800 Compare the B register to A	1/O REQ
		BRANCH TO MAJOR 61 MINOR 93 ON ND-GO	
		BRANCH TO MAJOR 61 MINOR 98	
1932	F305.N	FAULT IN CG8023 + OR DELTA_WY OR DELTA_WZ REC	
		ENABLE VERTICAL PARITY CHECK Stop Tape, display C register, nd-go light on	
		STUP TAPET DESPERT & REGISTERT NUTUR LIGHT UN	

ITESTICECISION   TEST/FAULT   SELF-TEST PROGRAM   REM	c (				
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	1				

I_INDICATORS	1_DISPLAY	L REPL	ACE_ASSEMBLIESI
INO GO	1	XXX 2ALALAL8	
1	1	[2A1A2A(14,10	5)
1		I2A1A3A06	

61	94	SPARE
61	95	SPARE
61	96	SPARE
61	97	SPARE

61 ' 98	ENABLE VERTICAL PARITY CHECK
61 99	END OF MAJOR TEST

ITESTICECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS I			
	JEC: TEST TROUMEN	i ieliaites i			
I_NO_I_LEVELINUMBERI		L			

62 00	BRANCH TO MAJOR 62 MINOR 3
62 01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
62 02	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
62 03	END OF MAJOR TEST

ITESTICECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS I
		•

63 00	BRANCH TO MAJOR 63 MINOR 3
63 01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
63 02	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
63 03	END OF MAJOR TEST

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TESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS	
I NO.I LEVEL I NUMBER I			

64 00	BRANCH TO MAJOR 64 MINOR 3
64 01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
64 02	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
64 03	END OF MAJOR TEST

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ITESTICECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS I
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		I I I
IND.I_LEVEL_I_NUMBERI		

65 00	BRANCH TO MAJOR 65 MINOR 3
65 01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
65 02	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
65 03	END OF MAJOR TEST

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ITESTIDECISION   TEST/FAULT    _NO_1 _LEVEL   NUMBER	SELF-TEST PROGRAM	I REMARKS I

66 00	BRANCH TO MAJOR 66 MINOR 3
66 01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
66 02	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
66 03	END OF MAJOR TEST

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356

TESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS I
I_NO.I_LEVEL_I_NUMBER		
67 00	BRANCH TO MAJOR 67 MINOR 3	
67 01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
67 02	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
67 03	END OF MAJOR TEST.	

		REMARKS
TESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS I
I_NO_L_LEVELINUMBERI		

68 00	BRANCH TO MAJOR 68 MINOR 3
68 01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
68 02	STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON
68 03	END OF MAJOR TEST

			-
ITESTICECISION   TEST/FAULT	SELF-TEST PROGRAM	REMARKS	1
		REHARKS	•
I NO.I LEVEL I NUMBER I			1

69 00	BRANCH TO MAJOR 69 MINOR 3
69 01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
69 02	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
69 03	END OF MAJOR TEST

TESTIDECISION	TEST/FAULT  NUMBER	I SELF-TEST PROGRAM	I REMARKS
*	*********	***************************************	*****************
*		CIU AND TACAN TEST CONTROL TESTS Majors 70 & 71, test t310 - t329	*
*	************		*
0 00		INITALIZE	
		DEFINE SELF TEST TAPE SET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST NCU CLOCK MODE (GTC003*)	
		ENABLE LOW LEVEL ON GTCOO1* RESET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST CIU CLOCK MODE (GTCOO3*) BRANCH TO MAJOR 70 MINOR 3	
70 01 70 02		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON Stop tape, display c register, no-go light on	
0 03 1	T310	TEST EOPA, TO TACAN, AREG->GTC902->QUN902->BREG, LSHD=VALID TAC ADDR=4, CHECK FOR CORRECT DECODE, CHECK FOR CIU MODE 2 RESET TST2(SIM NO-GO) PREVIOUS TEST = (61)T305	
0 04		SERIALLY LOAD THE B REGISTER WITH AAAAAAAA LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A01200 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF4FBF	EA3 ACTIVE = TACAN INTF SIM NO~GO, POSFIX PRESENT
		SIMULATE CIU EIP SERIAL TRANSFER OF 55555554 FROM A REGISTER TO B REGI	TEST Ster
2	F310.1	FAULT LOC WITHIN TEST T310 - FAULT IN CIUL CONTROL	
		IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES	   KCC053+
		IND GD I 4/1A1A3A25	KCC013* Sa0
			1 1
1	T310(CONT)	BRANCH TO MAJOR 70 MINOR 5 ON NO-GO Branch to Major 70 Minor 19	
70 05 2 70 06	T310.2	ISOLATE BETWEEN NO RESET OF TST2 & INVALID CIU OR TAC ADDR DECODE Set the I/O completé flag (gtcolo*)	RESET TST2 IF NOT RESET 1
		RESET THE I/O COMPLETE FLAG (GTCO10*) Branch to major 70 minor 7 on ND-Go Branch to major 70 minor 13	7310
70 07 3	T310.2.N	TEST DATA TRANSFER IN T310	

		I TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
70 08			COMPARE THE & REGISTER TO A5555555 BRANCH TO MAJOR 70 MINOR 9 ON NO-GO	
	4	F310.2.NG	DECODE OF INVALIC ADDR ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIES ND_GDBLANK12A1A3A11+5+91	   CC1094
70 09	4	F310.2.NN		   ACIO31 SƏO   KCCO47* => MRKO31 OR ACIO31   SƏ1
0 10 0 11 0 12			SPARE SPARE SPARE	
70 13 70 14	3	F310.2.G	TEST FOR DATA TRANSFER Compare the B register to A5555555 Branch to Major 70 Minor 15 on NO-Go	
	4	F310.2.GG	FAULT IN RESET OF TST2 BUT NO FAULT IN DATA TRANSFER ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSIDISPLAYIBEPLACE_ASSEMBLIES NO_GOIBLANKI2A1A3A113.151	1
10 15	4	F310.2.GN	FAULT IN CIUI IBT OR ACCO23 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I INDICATORS I DISPLAY	   ACC023 500 
70 16 70 17 70 18			SPARE SPARE SPARE	

		1 TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
70 19 70 20	1	T311	TEST DATA TRANSFEP IN T310 Compare the P Pegister to A5555555 Branch to Major 70 Minor 21 on ND-GO Branch to Major 70 Minor 37	
7021 7022	2	T311.N	TEST FOR NO TRANSFER OF DATA TO BREG Compare the B register to Aaaaaaa Branch to major to minor 23 on ND-Go Branch to major to minor 26	
70 23	3	F311.NN	FAULT IN DATA TRANSFEPED QUN902 -> RREG         ENABLE VERTICAL PARITY CHECK         STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON         INDIGATORS	ARB171* ACT031 INPUT TO CCT111* Sa TYC035* Sa1
0 24			SPARE	
70 25 70 26 70 27	3	T311.NG	SPARE TEST FOR AKA343* S@O => FAULT IN TAC INTF CLK C READ & COMPARE MISCELLANEOUS WORD 1 WITH A000002 LOGICALLY *AND* C REGISTER AND A REGISTER-RESULT IN B & C REGISTERS BRANCH TO MAJOR 70 MINOR 28 ON NO-GO BRANCH TO MAJOR 70 MINOR 31	
0 28	4	F311.NGN	FAULT IN INTF CLK C ENABLE VERTICAL PARITY CHECK STOP TAPE, CISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GOI4011A1A3A(24,25,27,28)I	AKA343* Sao
0 29 0 30			SPARE SPARE	
70 31 70 32	4	T311.NGG	TEST EOPA, AREG->GTC902->QUC902->BREG SERIALLY LOAD THE B REGISTER WITH AAAAAAAA LUAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A00200 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF0FBF SIMULATE CLU EIP SERIAL TRANSFER OF 55555551 FROM A REGISTER TO B REGIS COMPARE THE B REGISTER TO A555555 BRANCH TO MAJOR 70 MINOR 33 ON NO-GO	EA3 NOT ACTIVE = CIU INTF POSFIX PRESENT TEST TER

		I TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
	5	F311.NGGG	FAULT IN TACAN INTF CLK C OR GDATC ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
			IINDIGATORSI_DISPLAYIBEPLACE_ASSEMBLIESI IND_GOIBLANKI2A1A3A14,7,9,131I	BCI025* OR BCI026*
70 33	5	F311.NGGN	FAULT IN "TAC + CIU INTF SHIFT CLK" Enable vertical parity check Stop tape, display c register, no-go light on	
			I	GCI076* S@1
70 34 70 35 70 36			SPARE SPARE SPARE	
70 37 70 38	1	T312	TEST EOPA TO TACAN WITH INVALID TACAN ADDR = C, TEST GENERATION OF POSFIX GTC904 -> QUC904 -> ICP202* => SET NO-GO FLAG SERIALLY LOAD THE B REGISTER WITH AAAAAAAA LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A01200 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF0FBF SIMULATE CIU ETP SERIAL TRANSFER OF 5555555 FROM A REGISTER TO B REGIS	EA3 ACTIVE = TACAN INTF POSFIX PRESENT TEST
	2	F312.1	FAULT LOC WITHIN TEST 1312- FAULT IN DC SET OF NO-GO FLAG IINDICATERSI_DISPLAYIBEPLACE_ASSEMBLIESI I TEST_SET_FAULT_I6000012A1A1A13	
	1	T312(CONT)	BRANCH TO MAJOR 70 MINOR 48 ON NO-GO	
70 39 70 40	2	T312•2	TEST EOPA TO TAC, INVALID TAC ADDR = 6 => POSFIX => NO-GO SERIALLY LOAD THE B REGISTER WITH AAAAAAAA INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFFOFBF SIMULATE CIU EIP SERIAL TRANSFER OF 55555556 FROM A REGISTER TO B REGIS BRANCH TO MAJO? TO MINOR 41 ON NO-GO ERANCH TO MAJOR 70 MINOR 42	
70 41	3	F312.2.N	FAULT IN DECODE OF INVALID ADDR Enable vertical parity check Stop tape, display c register, ND-go light on	

		I TEST/FAULT	I SELF-TEST PROGRAM	REMARKS
			INOICATORSI DI SPLAYIREPLACE_ASSEMBLIESI INO_GOIBLANKI2A1A3A(5.9)	[CB081* S@1
70 42 70 43	3	T312.2.G	TEST INVALID ADDR = 0 => POSIFX => NO-GO SERIALLY LOAD THE B REGISTER WITH AAAAAAAA INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFFOFBF SIMULATE CIU EIP SERIAL TRANSFER OF 5555550 FROM A REGISTER TO B REGIS BRANCH TO MAJOR 70 MINOR 44 ON NO-GO BRANCH TO MAJOR 70 MINOR 45	
70 44	4	F312.2.GN	FAULT IN DECODE OF INVALID ADDR Enable vertical parity check Stop Tape, display C register, nd-go light on	
			IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GOIBLANKI2A1A3A09I	BC1085* SƏ1
70 45 70 46	4	T312.2.GG	TEST FOR CORRECT SIZE POSFIX PULSE, INVALID ADDR = 0 SERIALLY LOAD THE B REGISTER WITH AAAAAAAA INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF1FFF SIMULATE CIU EIP SERIAL TRANSFER OF 55555555 FROM A REGISTER TO B REGIS BRANCH TO MAJO® 70 MINOR 47 ON NO-GO	INH PROCEED RESET OF POSFI CNTR TER
	5	F312.2.GGG	FAULT IN GEN OF POSFIX ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYI	
70 47	5	F312.2.GGN	IND_GOI BLANKI2A1A3A17.8.9}I FAULT IN POSFIX PRESENT => NO-GO ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	ICP202* Sal
			IINDICATCBS1_DISPLAY1REPLACE_ASSEMBLIES INO GO I BLANK (2A1A1AO7 I112A1A3A18+9)	CYCOO2* SƏ1
70 48 70 49	1	T313	TEST MSB OF ADDR INH OF DATA TRANSFER => TRANSFER ALL ZERDS, MSHD OF BREG BYPASSED => A COMPARE THE B REGISTER TO A BRANCH TO MAJOR 70 MINOR 50 ON NO-GO BRANCH TO MAJOR 70 MINOR 53	

		I TEST/FAULT		REMARKS
0 50	2	F313.N	FAULT IN INH OF CCIIII* ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
				KCI036* S@1 ICI101 S@1
0 51			SPARE	
0 52				
0 53 0 54	1	T314	TEST EOPA TO TAC, INVALID TAC ADDR = 6 => POSFIX => NO-GO SERIALLY LOAD THE B REGISTER WITH AAAAAAAA LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH AO1200 INITIATE SELF TEST MODE 2-LGAD SELF TEST REGISTER WITH OFBFFFOFBF SIMULATE CIU EIP SERIAL TRANSFER OF 55555556 FROM A REGISTER TO B REGIS BRANCH TO MAJOR 70 MINOR 61 ON NO-GO BRANCH TO MAJOR 70 MINOR 55	EA3 ACTIVE = TACAN INTF POSFIX PRESENT TEST TER
0 55 0 56	2	T314.G	TEST CIU VALID ADDR = 2 => NO POSFIX => GO SERIALLY LOAD THE B REGISTER WITH AAAAAAAA LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH AO0200 INITIATE SELF TEST MCDE 2-LOAD SELF TEST REGISTER WITH OFBFFF0FBF SIMULATE CIU EIP SERIAL TRANSFER OF 55555552 FROM A REGISTER TO B REGIS BRANCH TO MAJOR 70 MINOR 57 ON NO-GO	EA3 NOT ACTIVE = CIU INTF POSFIX PRESENT TEST TER
	3	F314.GG	ICI053* INPUT TO BCI075 SƏL ENABLE VERTICAL PARITY CHECK STCP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
			I_INDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI INC_GOIBLANKI2AIA3A09I	
10 57	3	F314.GN	IC1053* Sel ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GDIBLANKI2A1A3A05I	
70 58 70 59 70 60			SPARE SPARE SPARE	
0 61	1	T 3 1 5	TEST INVALID TACAN ADDR = 5 => POSFIX => NO-GO	

		I TEST/FAULT	SELF-TEST PROGRAM	REMARKS
70 62			LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A01200 SERIALLY LOAD THE B REGISTER WITH AAAAAAAA INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFFOFBF SIMULATE CIU EIP SERIAL TRANSFER OF 55555555 FROM A REGISTER TO B REGIS	EA3 ACTIVE = TACAN INTF POSFIX PRESENT TEST TER
	2	F315.1	FAULT LOC WITHIN TEST T315 - FAULT IN RESET OF NO-GO FLAG	
	1	T315(CONT)	BRANCH TO MAJOR 70 MINOR 68 ON NO-GO	
70 63 70 64	2	T315.2	TEST CIU VALID ADDR = 1 => NO POSFIX => GO SERIALLY LOAD THE B REGISTER WITH AAAAAAAA LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A00200 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF0FBF SIMULATE CIU EIP SERIAL TRANSFER OF 55555551 FROM A REGISTER TO B REGIS BRANCH TO MAJOR 70 MINOR 65 ON NO-GO	
	3	F315.2.G	ICI054* INPUT TO BCI075 SƏ1 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSIDISPLAYI	
70 65	3	F315.2.N	ICIO54* SƏ1 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON I_INDICATCRSIDISPLAYIREPLACE_ASSEMBLIESI IND_GO	
70 66 70 67			SPARE SPARE	
70 68 70 69	1	T316	TACAN + CIU INVALID ADDR = 8 => POSFIX => NO-GC SERIALLY LOAD THE B REGISTER WITH AAAAAAAA INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFFOFBF SIMULATE CIU EIP SERIAL TRANSFER OF 555555558 FROM A REGISTER TO B REGIS BRANCH TO MAJOR 70 MINOR 73 ON NO-GO	
70 70	2	F316.G	FAULT IN DECODE OF INVALID ADDR ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON	

	I TEST/FAULT		I REMARKS
		INDICATORSI_DISPLAYIREPLACE_ASSEMBLIES   ND_GOIBLANKI2A1A3A(1+4+9+13)	CCI084* S@1 OR BCI026*
70 71 70 72		SPARE SPARE	
70 73 1 70 74	T317	TEST TACAN VALID ADDR = 4 => NO POSFIX, CHECK RESET OF NO-GO FLAG SERIALLY LOAD THE B REGISTER WITH AAAAAAAA LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH AO1200 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF0FBF SIMULATE CIU EIP SERIAL TRANSFER OF 55555554 FROM A REGISTER TO B REGIS BRANCH TO MAJOR 70 MINOR 75 ON NO-GO BRANCH TO MAJOR 70 MINOR 78	EA3 ACTIVE = TACAN INTF POSFIX PRESENT TEST TER
70752	F317.N	CYC004* SƏ1 ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSIDISPLAYIBEPLACE_ASSEMBLIESI IND_GDIBLANKIZAI33AI3I	
70 76 70 77		SPARE SPARE	
70781 7079	F318	TEST EOPA TO CIU, AREG->GTC902->QUC902->BREG, LSHD = VALID CIU ADDR = 1 =>NO POSFIX => GO SERIALLY LOAD THE B REGISTER WITH AAAAAAAA LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A00200 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF0FBF SIMULATE CIU EIP SERIAL TRANSFER OF 55555551 FROM A REGISTER TO B REGIS BRANCH TO MAJOR 70 MINOR 80 ON NO-GO BRANCH TO MAJOR 70 MINOR 83	EA3 NOT ACTIVE = CIU INTF POSFIX PRESENT TEST STER
70802 7081	T318.N	TEST DATA TRANSFER IN T318 Cumpare the B register to A5555555 Branch to Major 70 Minor 82 on NO-Go	
3	F318.NG	FAULT IN DECODE OF INVALID ADDR Enable Vertical Parity Check Stop Tape, Display C register, NO-GO light on	

TESTIDECISION			REMARS
		INDICATORSI_DISPLAYIREPLAGE_ASSEMBLIES IND GO I BLANK IZA1A3A69 IIII	[]  { €C1+42 INPST TC 801086* 08    IC1954* INPUT TO 801084 S∂
70 82 3	F318.NN	FAULT IN DATA TRANSFER QUC902 -> BREG ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON	
		INDICATORS I DISPLAY I	_  BCI102*
70831 7084	T319	TEST DATA TRANSFER IN T318 Compare the B pegister to a5555555 Branch to Major 70 Minor 85 on No-Go Branch to Major 70 Minor 88	
70852	F319.N	FAULT IN DATA TRANSFER QUC902 -> BRFG Enable vertical parity check Stop tape, display c register, ND-G0 light on	
		IINDICATORSI_CISPLAYIREPLACE_ASSEMBLIES NO_GOI_XXXXXXXXXI2A1A3AG7	_1 _1 ACI014*
70 86 70 87		SP AR E SP AR E	
70 88 1 70 89	T320	TEST CIU INVALID ADDR = 4 => POSFIX => NO-GO LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A00200 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF0FBF SIMULATE CIU EIP SERIAL TRANSFER OF 55555554 FROM A REGISTER TO B REG BRANCH TO MAJOR 70 MINOR 93 ON NO-GO	EA3 NOT ACTIVE = CIU INTF POSFIX PRESENT TEST ISTER
70902	F320.G	FAULT IN DECODE OF INVALID ACOR ENABLE VERTICAL P/RITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES IND_GOIBLANKI2A1A3A09	 _  BCI086*
70 91 70 92		SP AR E SP AR E	
70 93 1	T321	TEST FOR GENERATION OF PROPER WIDTH POSFIX PULSE, INVALID CIU ADDR = 4	

TESTIDECTSION   TEST/FAULT	I SELF-TEST PROGRAM	I REMARKS
70 94	LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A00200 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFFIFFF SIMULATE CIU ETP SERTAL TRANSFER OF 55555554 FROM A REGISTER TO B REGI BRANCH TO MAJON 70 MINOR 98 ON NO-GO	EA3 NOT ACTIVE = CIU INTF INM PROCEED RESET OF POSFIX CNTR STER
70 95 2 F321.G	FAULT POSFIX GENFRATOR OR RECEIVER => NO SET OF NO-GO ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATOBSIDISPLAYIREPLACE_ASSEMBLIES IND_GOREANK12A1A3A17.8.9.10.12)	1
70 96 70 97	SPARE SPARE	
70 98 70 99	ENABLE VERTICAL PARITY CHECK END OF MAJOR TEST	

	SION   TEST/FAULT VELNUMBEB		I REMARKS I
71 00		INITALIZE DEFINE SELF TEST TAPE SET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST NOU CLOCK MODE (GTC003*) ENABLE LOW LEVEL ON GTC001* RESET INHIBIT INCREMENT CP FLAG & ENABLE SELF TEST CIU CLOCK MODE (GTC003*) BRANCH TO MAJOR 71 MINOR 3	
71 01		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
71 02 2	F331.1	FAULT IN 558 OF MARC STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		I INDICATORS I DISPLAY I REPLACE ASSEMBLIES	
71 C3 1 71 O4	1922	TEST LLOPR => RESET TST2(SIM NO-GO), RREG=OFFFFFF->GTC903->QUC903->BREG, MSHD AREG = VALID CIU ADDR = B => NO POSFIX => GO LGAD A REGISTER WITH 05555555 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFF0F7F LGAD DISCRETE INPUT WORD (ELP/EOP CODE) WITH A00200 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF57FF	ROM->RIM EA3 NOT ACTIVE = CIU INTF INH PROCEED RESET OF POSFIX CNTR, CIU ROLK EN INH, SIM
		SERIAL SHIFT B TO B REGISTER-CHECK ADDRESS B	ND GO
2	F32 <b>2</b> •1	FAULT LOC WITHIN TEST T322 - CIU2 HANGUP	KCC014* S@0
1	F322(CONT)	BRANCH TO MAJOP 71 MINOR 5 ON NO-GO Branch to Major 71 Minor 11	
71 05 2 71 06	T322.2	ISOLATE BETWEEN NO RESET OF TST2 AND GEN POSFIX Set the I/O complete Flag (gtcolo*) Reset the I/O complete Flag (gtcolo*) Branch to Major 71 Minor 7 on No-Go	RESET TST2 IF NO RESET IN T322
à	F322+2+G	FAULT IN CIU2 IBT OR FF ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	

TESTIDECISION	I TEST/FAULT	I SELF-TEST PROGRAM	REMARKS
		IINDICATORSI_DISPLAYI	K CC0 14*
71 07 2	F322.2.N	FAULT IN TRANSFER OF AREG -> CIU ADDR ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATOBSI_DISPLAYIBEPLACE_ASSEMBLIESI INO_GOIBLANKI2A1A3A11I	CCC025*
71 08 71 09 71 10		SPARE SPARE SPARE	
71 11 1 71 12	T 3 2 3	TEST DATA TRANSFER IN 1322 Compare the B register to A5555555 Branch to Major 71 minor 13 on NO-Go Branch to Major 71 minor 20	
71 13 2	F323.N	FAULT IN DATA TRANSFER BREG->GTC903->QUC903->BREG ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		I _ INDICATORS   CISPLAY	ACC016* 5@1
		NO GO   12525252212A1A1A1(6,20)     221A3A(9,16)	I ATO 25
		NO GO   52525252512A1A1A(16,20)    1 2A1A3A(5,8,9,16)	ARB063* \$01
		INC GO IXXXXXXXXXXI2A1A1A07 I II2A1A3A113+161I	CYC015* SƏ1
71 14 71 15 71 16 71 17 71 18 71 19		SPARE SPARE SPARE SPARE SPARE SPARE	
71 20 1 71 21	T324	TEST EIOPB BOTH "CIU BCLK" AND "TAC+CIU INTF SHIFT CLK+ CHECK ADDR DECODE OF VALID CIU ADDR = A LOAD A REGISTER WITH 00055555 INITIATE SELF TEST MCDE 1-LOAD SELF TEST REGISTER WITH 0FBFFF0F7F LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A00200	ROM->RIM Ea3 NOT ACTIVE = CIU INTF

	I TEST/FAULT		I REMARKS
			INH PROCEED RESET OF POSEL ONTR
1 22 2	F324.N	FAULT IN DECODE OF INVALID ADDR ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI IND_GOIBLANKI2A1A3A09I	ICI053* INPUT TO CCI084 Sal
71 23 71 24 71 25 71 26 71 27 71 27 71 28		SPARE SPARE SPARE SPARE SPARE SPARE	
71 29	T325	SPARE TEST NUMBER AND LOCATION BRANCH TO MAJOR 71 MINOR 38	
71 30 71 31 71 32 71 33 71 34 71 35 71 36 71 37		SPARE SPARE SPARE SPARE SPARE SPARE SPARE SPARE	
7138 1 7139	T326	TEST EIOPB (NCU ECP), BREG->GTC902->QUN902->BREG, CIU BCLK EN, VALID TAC ADDR = 4 LOAD A REGISTER WITH 00055555 INITIATE SELF TEST MODE 1-LOAD SELF TEST REGISTER WITH OFBFFF0F7F LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A01200 INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFF1BFF	ROM->RIM EA3 ACTIVE = TACAN INTF INH PROCEEC RESET OF POSFI CNTR, INH TAC+CIU INTF
		SERIAL SHIFT B TO B REGISTER-CHECK ADDRESS 4 Branch to Major 71 minor 40 on NO-Go Branch to Major 71 minor 47	SHIFT CLK
1 40 2	F326.N	FAULT IN AREG -> TAC ADDR OR ADDR DECODE ENABLE VERTICAL PARITY CHECK	

TESTIDECISION			I REMARKS
		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES ND_GOIBLANKI2A1A3A19,111	l i
71 41 71 42 71 43 71 44 71 44 71 45 71 46 71 47 1	T 3 2 7	TEST DATA TRANSFER IN 1326	
71 48	1321	COMPARE THE B REGISTER TO A0055555 BRANCH TC MAJOR 71 MINOR 49 ON NO-GO BRANCH TO MAJOR 71 MINOR 56	
71 49 2	F327.N	FAULT IN BREG -> GTC902, OR INH OF TAC+CIU INTF SHIFT CLK ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
		INDICATORS   DISPLAY   BEPLACE ASSEMBLIES NO_GOI 177652525212A1A3A11 NO_GOI 2525512A1A3A11 NO_GOI 2525512A1A3A11 NO_GOI 2525512A1A3A07  I 241A3A(13.16)	IRB144 INPUT TO CCC024* Sal
71 50 71 51 71 52 71 53 71 54 71 55		SPARE SPARE SPARE SPARE SPARE SPARE	
71 56 1	T328	TEST SERIAL TRANSFER TO NCU TAC INTF, DATA REQ A, BREG->GTNO02->QUU002(S.T. TAC RECJ->ICTI31->BREG, BREG UNCHANGED EXCEPT BIT #1 (0->1) LOAD DISCRETE INPUT WORD (EIP/EOP CODE) WITH A00200	EA3 NOT ACTIVE = CIU INTF
		SERIALLY LOAD THE B REGISTER WITH AAAAAAA INITIATE SELF TEST MCDE 2-LOAD SELF TEST REGISTER WITH OFBFFFODFE SIMULATE CIU EIP SERIAL TRANSFER OF AAA55554 FROM A REGISTER TO B REGI COMPARE THE B REGISTER TO AAAAAAAI BRANCH TO MAJOR 71 MINOR 58 ON NO-GO BRANCH TO MAJOR 71 MINOR 67	EN SIM TAC OD TO BREG, DATA REQ A
73 D8 - 2	F328.N	FAULT IN SERIAL TRAMSFER TO NCU TAC INTE ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	

	DN I TESTZFAULT	SELF-YEST PROCEAM	I REMARKS
		INCLCATORS       IDISPLAY       EEPIACE ASSEMBLIES         INC_60       I.125252524112A1(3A(12.14)         INO_60       S2525253612A1AAA(12.14)         INO_60       I.25252523612A1AAA(12.14)         INO_60       I.26112A1A3A09         INO_60       I.26112A1A3A05         INO_60       I.12.1A1(3,4,7)         INO_60       I.12.1A1(3,4,7)         INO_60       I.12.1A1(3,4,7)         INO_60       I.12.1A3A(5,9,11,13,14,16)	AYCOC8* 501   QUUOO2 501   IYCOO7* 501
71 59 71 60 71 61 71 62 71 63 71 64 71 65 71 66		SPARE SPARE SPARE SPARE SPARE SPARE SPARE SPARE	
71 67 1 71 68	T329	TEST SERIAL TRANSFER TO NCU TAC INTF, DATA REQ B, BREG UNCHANGED EXCEPT BIT #2 (0->1) SERIALLY LOAD THE B REGISTER WITH AAAAAAAO INITIATE SELF TEST MODE 2-LOAD SELF TEST REGISTER WITH OFBFFFOEFE SIMULATE CIU ETP SERIAL TRANSFER OF AAA55554 FROM A REGISTER TO B REGI COMPARE THE B REGISTER TO AAAAAAA2 BRANCH TC MAJOR 71 MINOR 69 ON NO-GO BRANCH TO MAJOR 71 MINOR 98	EN SIM TAC OC TO BREG, DATA Req B Ster
71 69 2	F329.N	FAULT IN SERIAL TRANSFER TO NCU TAC INTF ENABLE VERTICAL PARITY CHECK STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDIGATORSI_DISPLAYIREPLACE_ASSEMBLIES INO GO I 212A1A1A07 II2A1A3A(12.14) INO GO IXXXXXXXXXX2212A1A1A01 II2A1A3A(15.8.12.13.14)	   ANIO45* S@1 OR INIO22   
71 70 71 71 71 72 71 73 71 74 71 75 71 76 71 76 71 78 71 78 71 79		SPARE SPARE SPARE SPARE SPARE SPARE SPARE SPARE SPARE SPARE	

TESTICECISION   TEST/FAULT	SELF-TES	T PROGRAM	I REMARKS I
71 80	SPARE		
71 81 71 82	SPARE SPARE		
71 83	SPARE		
71 84 71 85	SPARE		
71 85	SPARE SPARE		
71 87	SPARE		
71 88 71 89	SPARE SPARE		
71 90	SPARE		
71 91	SPARE		
71 92 71 93	SPARE SPARE		
71 94	SPARE		
71 95	SPARE		
71 96 71 97	SPARE SPARE		

 71
 98
 ENABLE
 VERTICAL
 PARITY
 CHECK
 71
 99
 END OF
 MAJOR
 TEST

ITESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS I	
I_NO_1LEVEL1NUMBEB	l		

72 CO	BRANCH TO MAJOR 72 MINOR 3
72 01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
72 02	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
72 03	END OF MAJOR TEST

TESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS I
I_NO.ILEVELINUMBERI		

73 00	BRANCH TO MAJOR 73 MINOR 3
73 01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
73 02	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
73 03	END OF MAJOR TEST

TESTICECISION   TEST/F		I REMARKS	
74 00	BRANCH TO MAJOR 74 MINOR 3		
74 01 2 F330.1	BBC234* SQ1 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON		
	IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES IND_GOIBLANKIIAIAIAI2I123I	 	
74 02 74 03	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON END OF MAJOR TEST		

TESTIDECISION		SELF-TEST PROGRAM	I REMARKS
75 00		BRANCH TO MAJOR 75 MINOR 3	
75 01		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
75 02		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
75 03 1	T 3 30	TEST 358 OF MABC BRANCH TO MAJOR 54 MINDR 1	
75 04		END OF MAJOR TEST	

ITESTICECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS I	

76 00	BRANCH TO MAJOR 76 MINOR 3
76 01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
76 02	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
76 03	END OF MAJOR TEST

ITESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS I
I_NO.1_LEVEL_1NUMBER1		

77 00	BRANCH TO MAJOR 77 MINOR 3
77 01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
77 02	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
77 03	END OF MAJOR TEST

ITESTICECISION   TEST/FAULT	SELF-TEST PROGRAM	REMARKS
INDAL_LEVEL_1NUMBERI		
Langer - reaction - and the second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second second se		

78	00	BRANCH TO MAJOR 78 MINOR 3
78	01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
78	02	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
78	03	END OF MAJOR TEST

TESTIDECISION   TE	ST/FAULT 1 NUMBER	SELF-TEST PROGRAM	REMARKS
79 00		AJOR 79 MINOR 3	
79 01 79 02		DISPLAY C REGISTER, NO-GO LIGHT ON	
79 03	ENC OF MAJO	R TEST	

	LEVEL	I TEST/FAULT	SELF-TEST PROGRAM	REMARKS
80 00	2	F332.2	BBC032* \$@0	
			IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI IESI_SEI_FAULI_I210000000011A1A1A121.2231I	
			PUNCH TAPE LEADER 12 INCHES LONG	
80 01			BRANCH TO MAJOR 80 MINOR 3 Stop Tape, display C register, nd-go light on	
80 02			STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
80 03	1	T332	TEST MSB OF MABC PREVIOUS TEST = (54)T331 BRANCH TO MAJOR 89 MINOR 2	
80 04			END OF MAJOR TEST	

ITESTIDECISION   TEST/FAULT     NO.1 LEVEL 1 NUMBER	SELF-TEST PROGRAM	I REMARKS	
81 00 81 01 81 02 81 03	BRANCH TC MAJOR 81 MINOR 3 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON ENC OF MAJOR TFST		

ITESTICECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
I_NO.I_LEVEL_INUMBEBI		

82 00	BRANCH TO MAJOR 82 MINOR 3
82 01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
82 02	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
82 03	END OF MAJOR TEST

TESTICECISION   TEST/FAULT	SELF-TEST PROGRAM	R EMARKS
I_UU&IkLYLkIUVUULBI		

83	00	BRANCH TO MAJOR 83 MINOR 3
83	01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
83	02	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
83	03	END OF MAJOR TEST

ITESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	REMARKS 1
NC.L LEVEL L NUMBER		
I_BEAL-LEVEL_INONDEEI		

84	00	BRANCH TO MAJOR 84 MINCR 3
84	01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
84	02	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
84	03	END OF MAJOR TEST

ITESTICECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS I
I_NO_I_LEVEL_I_NUMBERI		

85 00	BRANCH TO MAJOR 85 MINOR 3
85 01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
85 02	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
85 03	END OF MAJOR TEST

TESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	REMARKS

86 00	BRANCH TO MAJO# 86 MINOR 3
86 01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
86 02	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
86 03	END OF MAJOR TEST

ITESTICECISION   TES	T/FAULT ! UMBER	SELF-TEST PROGRAM		I REMARKS I
*****	****	******	****	* * * * * * * * * * * * * * * * * * * *
*				*
*	THIS MAJOR	NUMBER ALSO USED FOR TEST/FAULT LOC AFTE	R MAJOR 99	*
*				*
****	******	******	***	****
87 00	BRANCH TO MAJO	R 87 MINOR 3		
87 01		PLAY C REGISTER, NO-GO LIGHT ON		
87 02		PLAY C REGISTER. NO-GO LIGHT ON		
87 03	END OF MAJOR T	· · · · · · · · · · · · · · · · · · ·		

ITESTICECISION   TEST/FAULT	SELF-TEST PROGRAM	REMARKS 1
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88	00	BRANCH TO MAJOR 88 MINOR 3
88	01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
88	02	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
88	03	END OF MAJOR TEST

TESTIDECISION   TES	T/FAULT   UMBER	SELF-TEST PROGRAM	REMARKS
89 00	BRANCH TO M	AJOR 89 MINOR 3	
89 01	STOP TAPE, I	DISPLAY C REGISTER, NO-GO LIGHT ON	
89 02			
89 03	END OF MAJO	RITEST	

ITESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS I
I_NO_L_LEVEL_LNUMBERL		LI
90 00	BRANCH TO MAJOR 90 MINOR 3	
90 01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHY ON	
90 02	STOP TAPE, DISPLAY C REGISTER, ND-GQ LIGHT ON	
90 03	END OF MAJOR TEST	

TESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	REMARKS
I_NO.I_LEVEL_INUMBERI		
91 00	BRANCH TO MAJOR 91 MINOR 3	
91 01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
91 02	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
91 03	END OF MAJOR TEST	

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TESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS I
92 00 92 01 92 02 92 03	BRANCH TO MAJOR 92 MINOR 3 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON END OF MAJOR TEST	

ITEST/ECCISION | TEST/FAULT | SELF-TEST PROGRAM | REMARKS

93	00	BRANCH TO MAJOR 93 MINOR 3
93	01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
93	02	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON
93	03	END OF MAJOR TEST

ITESTIDECISION   TEST/FAULT	SELF-TEST PROGRAM	REMARKS
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94 00	BRANCH TO MAJOR 94 MINOR 3	
94 01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
94 02	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
94 03	END OF MAJOR TEST	

ITESTICECISION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS
95 00 95 01 95 02 95 03	BRANCH TO MAJOR 95 MINOR 3 STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON END OF MAJOR TEST	

	DECISIO	N   TEST/FAULT	I SELF-TESY PROGRAM I REMARKS I
96 00	2	F337.1	BBC031* INPUT TO MBC061 S@1 IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES IFST_SEY_EAULI_12100000000011A1A1A22
96 01 96 02 96 03			PUNCH TAPE LEADER 12 INCHES LONG BRANCH TO MAJOR 96 MINOR 3 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON END OF MAJOR TEST

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ŵ.	THIS MAJOR NUMBER ALSO USED FOR TEST/FAULT LOC AFTER MAJOR 99	9 *
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	20 ANCH TO NA 100 07 MINOD 2	
	END OF MAJOR TEST	
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TESTIDECISION   TEST/FAULT ( NO.1 LEVEL 1 NUMBER 1	SELF-TEST PROGRAM	I REMARKS
98 00 98 01 98 02 98 03	BRANCH TO MAJOR 98 MINOR 3 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON END OF MAJOR TEST	

TESTICECISION   TEST/FAU		I REMARKS I
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*	THIS MAJOR NUMBER ALSO USED FOR TEST/FAULT LOC AFTER MAJOR	99 *
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****	**********	*****
9 <b>9</b> 00	BRANCH TO MAJOR 99 MINOR 3	
99 01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
99 02	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
99 03	END OF MAJOR TEST	

FESTI DECISIO NO.I. LEVEN	IN TEST/FA		REMARK S
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	*		*:
	*	MAJOR BRANCH TEST, MSB & 2SB OF MABC - FOLLOWING MAJORS ARE R	REPEATED: *
	÷	17, 57, 87, 97, 99	3 <sub>7</sub>
	* M	AJORS HEX C7, C8, C9 WILL BE DISPLAYED IN MAJOR DISPLAY AS SMALL U7 U	J8 U9 RESPECTIVELY *
	*		<i>\$</i>
	****	***************************************	/**:**********************************
7 00		BRANCH TO MAJOR 17 MINOR 3	
7 01 1	1337	TEST INPUT TO MBC061 FOR Sal	
		PREVIOUS TEST = $(HEX C9)T336$	
		BRANCH TO MAJOR 97 MINOR 2	
7 02		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
1 02		STOP PAPER DISPLATE REGISTERY NOTO LIGHT ON	
7031	T335	TEST MSB & 2SB OF MABC	
		PREVIOUS TEST = (80)T332	
		LOAD A REGISTER WITH 002C7	BR ADDR = HEX C7 2
		BRANCH TO ADDRESS LOCATION IN A REGISTER	

TESTICECTSION   TEST/FAULT NO.1_LEVEL_1NUMBER	SELF-TEST PROGRAM	REMARKS
7 00 7 01	BRANCH TO MAJOR 3 MINOR OO STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
7 02 2 F335.1	BBC031* S01 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
	IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIESI NO_GOIBLANKIIAIAIA21I	
7 03	END OF MAJOR TEST	

TESTIDECTSION		SELE-TEST PROGRAM	REMARKS
57-00		BRANCH TO MAJOR 57 MINOR 3	
57 01 2	F336•1	BBC133* S&1 STOP TAPE, DISPLAY C REGISTER, ND-GO LIGHT ON	
		IINDICAIDESI_DISPLAYIBEPLACE_ASSEMBLIESI INC_GOIBLANKIJAIAIAI21.23I	
57 02 57 03		STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON END OF MAJOR TEST	

TEST CECISION   TEST/FAULT  _NO+1_LEVEL1NUMBER	I SELF-TEST PROGRAM	I REMARKS
87 00 2 F338.1	BBC132* INPUT TO MBC061 SƏ1 IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES IIESI_SET_FAULT_12100000000011A1A1A22	1
87 01	PUNCH TAPE LEADER 12 INCHES LONG BRANCH TO MAJOR 87 MINOR 3 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON	
87 02 2 F335.2	EBC132* S@1 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYIREPLACE_ASSEMBLIES IND_GOIBLANKI1A1A1A21	1
87 03	END OF MAJOR TEST	

TESTICECTSION   TEST/FAULT	SELF-TEST PROGRAM	I REMARKS I
97 00	BRANCH TO MAJOR 97 MINOR 3	
97 01 2 F336.2	BBC032* SØ1 STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON IINDICATORSI_DISPLAYIBEPLACE_ASSEMBLIES IND_GOIBLANKIIAIAIA(21,23)	
97 02 1 T338	TEST INPUT TO MBCO61 FOR SƏ1 PREVIOUS TEST = (2ND 17)T337 LOAD A REGISTER WITH OO1C7 BRANCH TO ADDRESS LOCATION IN A REGISTER	BR ADDR = HEX C7 1
97 03	END OF MAJOR TEST	

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99 98				
99 99	1	T340	END OF TAPE TEST, PREVIOUS TEST = (2ND 97)T338 END OF TAPE FLAG	

END OF MAJOR TEST

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	PUNCH TAPE LEA	ACER 12 INCHES LONG		
99 00	PUNCH TAPE COU Branch to Majo		ADDR = HEX C7	
99 01	NOT A TEST LOC - Branch to Majo	- BRANCH TO END OF TAPE TEST T340 DR 99 MINOR 00	BR TO SECOND MAJOR 99	
99 02 99 03	END OF MAJOR 1	TEST		

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ITESTICECISION   TEST/FAULT	SELF-TEST PROGRAM	REMARKS 1
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HEX C8

PUNCH TAPE LEADER 12 INCHES LONG

	PUNCH TAPE CODES - 08 0C	ADDR	=
<b>99</b> 00	BRANCH TO MAJOR 99 MINOR 3		
99 01	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON		
99 02	STOP TAPE, DISPLAY C REGISTER, NO-GO LIGHT ON		
99 03	END OF MAJOR TEST		

_NO.1LEVE	ON   TEST/FAUL		I REMARKS
		PUNCH TAPE LEADER 12 INCHES LONG	
9 00 9 01 9 02		PUNCH TAPE CODES ~ @9 @C Branch to Major 99 Minor 3 Stop tape, display c register, no-go light on Stop tape, display c register, no-go light on	ADDR = HEX C9
9031	T336	TEST MSB & 2SB OF MABC Previous test = (2ND 17)t335 Branch to Major 17 minor 1	
		PUNCH TAPE LEADER 12 INCHES LONG	
	************	****	**************
	*	MAJOR ADDR = HEX FF => MAJOR DSPL = BLAN E 1023 NOOPS IN THIS MAJOR TO CAUSE PROCEED ERROR IF CONTROL	νκ *
	******	***************************************	*********
00		PUNCH TAPE CODES - 2F 2F	ADDR = HEX FF
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01 02 03 04 05 06 07 07 08 09			
01 02 03 04 05 05 06 07 07 08 07 08 09 09 010 11			
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01         02         03         04         05         06         07         08         09         10         11         12         13         14         15         16         17			
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9       01         9       02         9       03         9       04         9       05         3       06         9       07         9       08         9       09         9       10         9       11         9       12         9       13         9       14         9       15         9       16         9       17         9       18         9       19         9       20			
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JOB RUN ON NCCITS FAULT ISOLATION COMPILER - E JOB DATE: 02/18/71 By Order of the Secretary of the Army:

W. C. WESTMORELAND, General, United States Army, Chief of Staff.

Official:

VERNE L. BOWERS, Major General, United States Army, The Adjutant General.

Distribution:

To be distributed in accordance with DA Form 12-31, Direct and General Support maintenance requirements for OV-1D and U-21 aircrafts.

## **CHAPTER 5**

## FINAL ILLUSTRATIONS

This chapter contains the color code diagram for MIL-STD resistors and capacitors and all foldout illustrations referenced in previous chapters.

U.S GOVERNMENT PRINTING OFFICE 1973 520-022/721 1-3

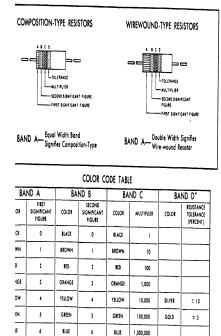
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Figure 5-2 NOT USED

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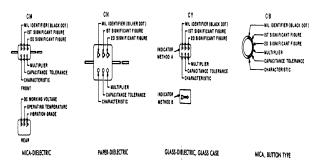
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### COLOR CODE MARKING FOR MILITARY STANDARD RESISTORS

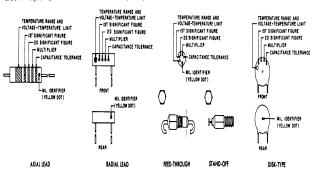


#### COLOR CODE TABLES

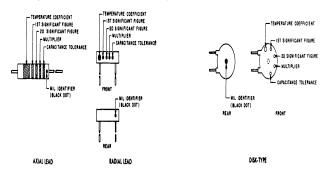
TABLE I - For use with Group I, Styles, CM, CN, CY and CB



GROUP II Capacitors, Fixed Ceramic-Dielectric (General Purpose) Style CK



GROUP III Capacitors, Fixed, Ceramic-Dieletric (Temperature Compensating) Style CC



#### COLOR CODE TABLES

### TABLE I - For use with Group I, Styles CM, CN, CY and CB

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		110	rig		CM	CN	α	CB	CM	CN	CY	CB	CM	CM	CH
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BOWN		1	1	10					1	E	-	1			
IED		1	2	100	± 2%		2 2 %	± 2%	c	-	c	-	++	-55' 10 +45'C	
ORANGE		3	1	1,000		± 30%			0	-		0	300		
TELLOW		4	4	10,000					1	-		-	++	-55" 10 + 125"C	10-2,000 cp
GREEN		5	5		2.5%			-	1	-		-	500		10-2,000 (6
ALVE		6	6						-	-				-55° 10 +150°C	
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GOLD				01			± 5%	± 5%							
SILVER	CN				± 10%	± 10%	± 10 %	= 10%	-						

#### TABLE II For use with Group II, General Purpose, Style CK

							IE	empei	ature C	om	pe	nsatin
COLOR	TEMP, RANGE AND VOLTAGE - TEMP LIMITS <sup>3</sup>		SIG	MULTIPLIER	CAPACITANCE TOLERANCE	MIL ID		COLOR	TEMPERATURE COEFFICIENT*	1st SIG FIG	2nd SIG FIG	MULTIPLIER
NACK		0	0	1	± 10%			RACK	0	0	0	
BOWN	AW	1	1	10	± 10%			BOWN	- 10	+	1	10
RED	AX	1	2	100		-		HED	~10	1	1	
OBANGE	si	3	3	1,000				ORANGE	- 150		-	100
YELLOW	AY	4	4	10,000		α				3	3	1,000
GREEN	a	5	5	-		<u> </u>		YELLOW	~ 220	1	+	
RUE	W	6	6					GREEN	- 330	5	\$	
PUBPLE		-						ILVE	~ 470	6	6	
(VIOLET)		1	,					PUTPLE	-750	,	,	
GIEY		1	1					GREY		1	1	0 01
WHITE		,	9			-		WHITE		,	,	01
GOLD								GOLD	+100			
SILVER								SILVER		-		

TABLE III - For use with Group III. npensating. Style CC CAPACITANCE TOLERANCE 2nd

> Capacitances over 10auf Copecitances 10auf or less

± 5% ± 0.5evf

10 ± 1%

100 ± 2% ± 0 25wd

9 01 ± 10% ID

± 2 0ml (C

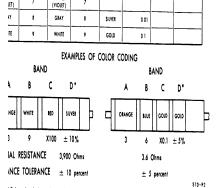
±10wf

1. The multiplier is the number by which the two;significant [SIG] figures are multiplied to obtain the copacitance in uuf.

2 Letters indicate the Characteristics designated in applicable speafications MIL-C-5, MIL-C-91, MIL-C-11272, and MIL-C-10950 respectively

3 Letters indicate the temperature range and voltage-temperature limits designated in MIL-C-11015

4 Temperature coefficient in parts per million per degree centigrade



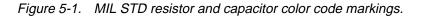
 $1\,\text{D}$  is omitted, the resistor tolerance is  $\pm\,20\%$  , and the resistor is not Mil-Std.

PLE

1

PURPLE

1



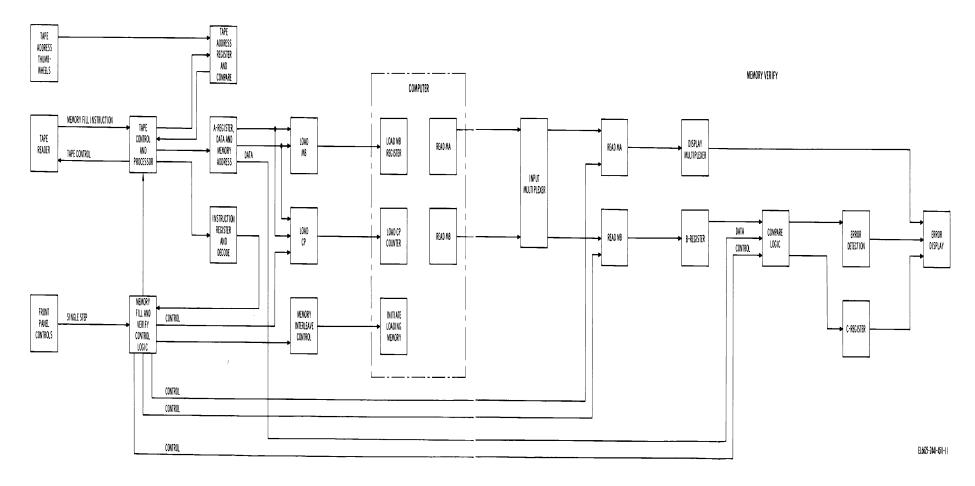


Figure 5-3. Memory fill and verify, block diagram.

MEMORY FILL

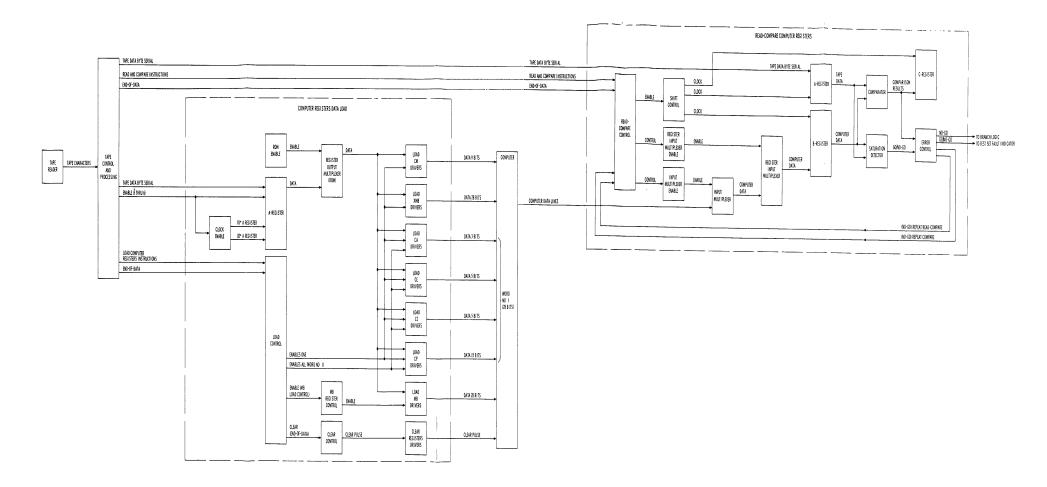


Figure 5-4. Load and read-compare, functional block diagram.

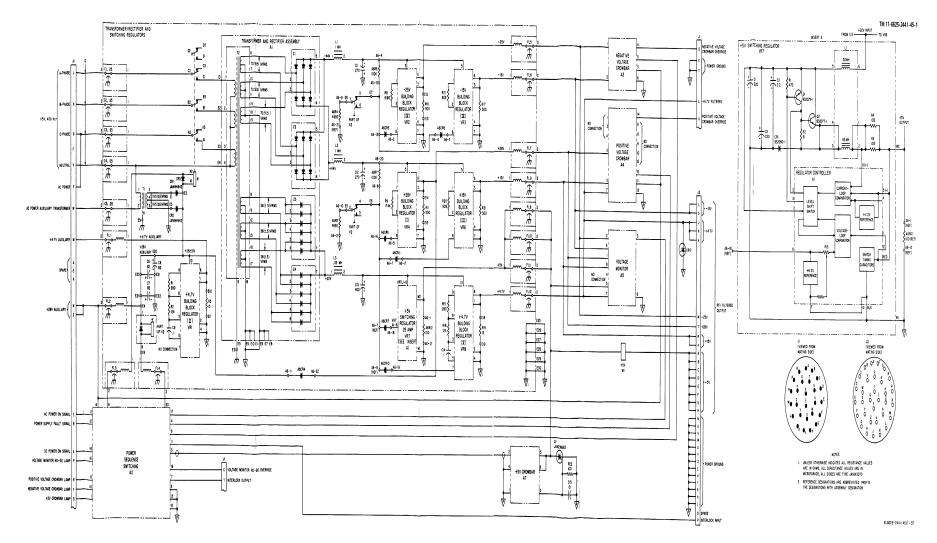
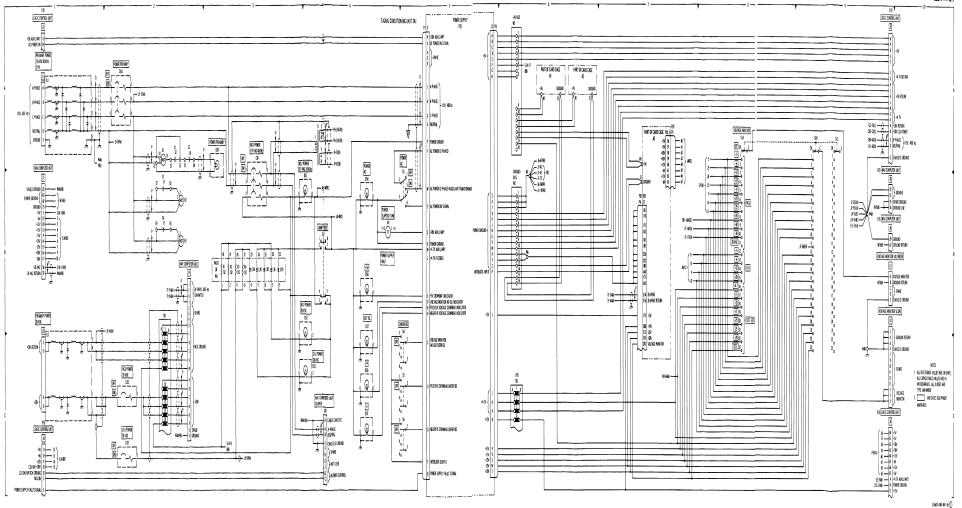


Figure 5-5. Power supply 2A1PS1, functional schematic diagram







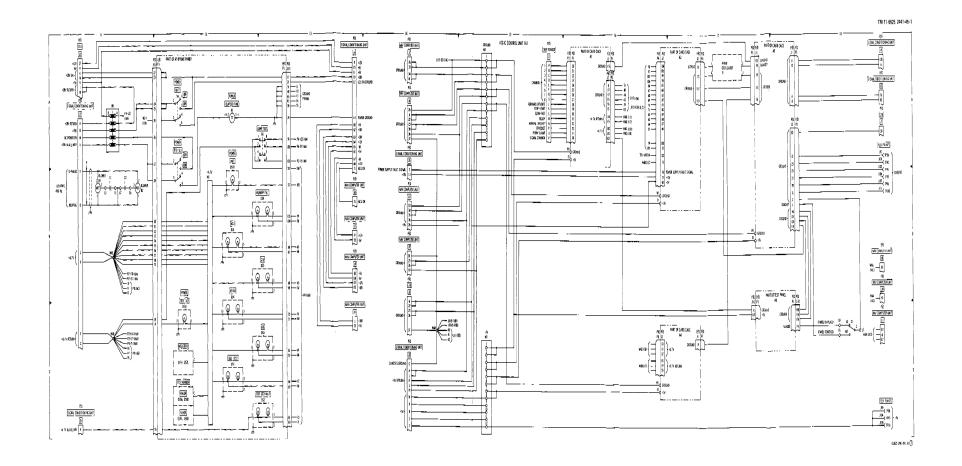


Figure 5-6 *Q*. Power control and distribution, functional schematic diagram (part 2 of 2).

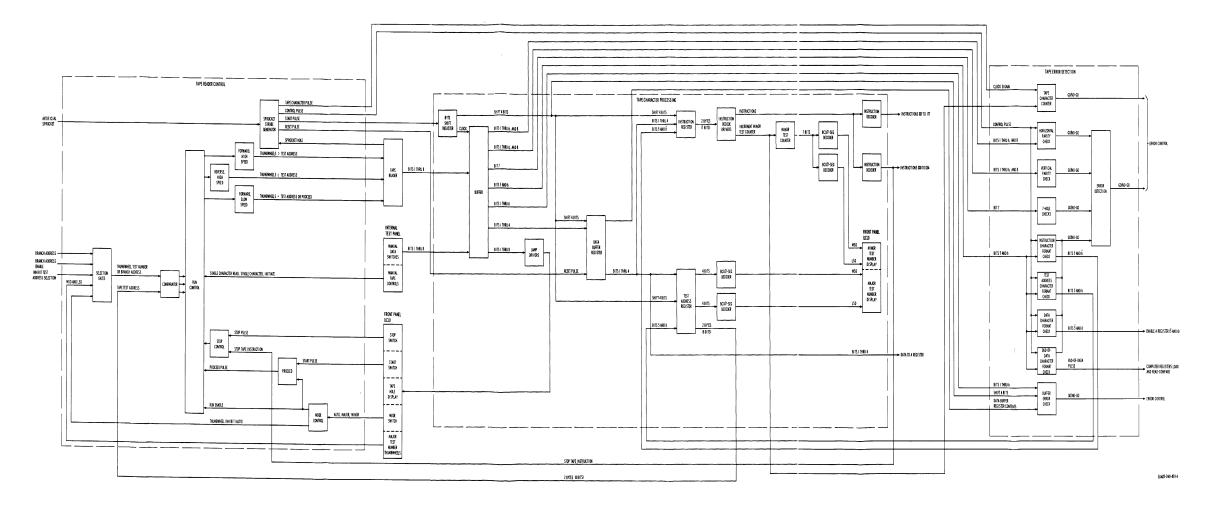


Figure 5-7. Tape control and processing, functional block diagram.

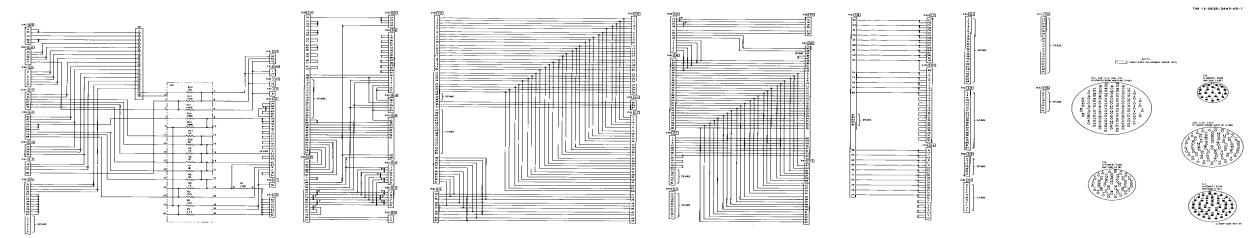


Figure 5-8. Adapter, Self Test MX-386 schematic diagram.

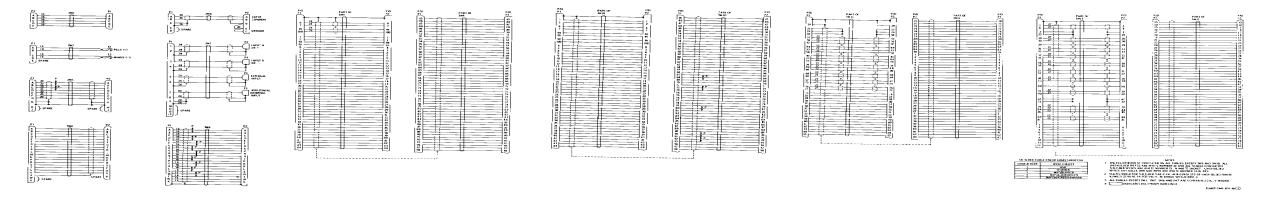


Figure 5-9 <sup>①</sup>. Special purpose electrical cable assembly schematic diagram (part 1 of 3).

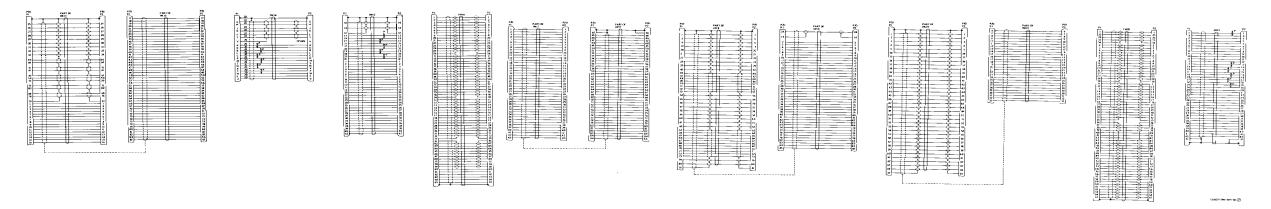
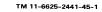


Figure 5-9 <sup>(2)</sup>. Special purpose electrical cable assembly, schematic diagram (part 2 of 3).



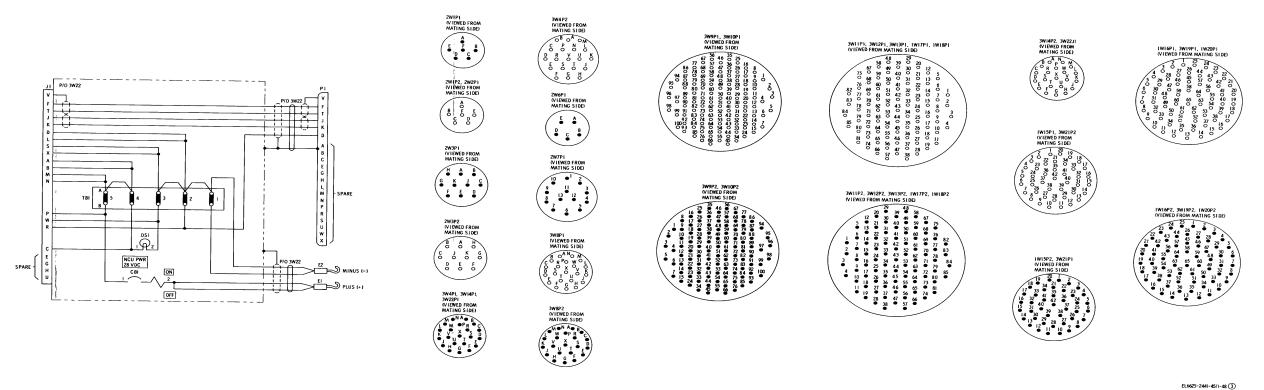


Figure 5-9 3. Special purpose electrical cable assembly, schematic diagram (part 3 of 3).

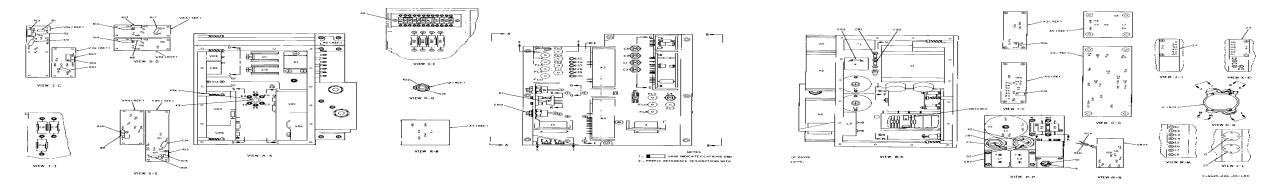


Figure 5-10. Power supply 2A1PS1, parts location diagram.